Radiation Report

TPS7H5030-SP Neutron Displacement Damage (NDD) Characterization Report

TEXAS INSTRUMENTS

ABSTRACT

This report presents the effect of neutron displacement damage (NDD) on the TPS7H5030-SP device. This platform of devices show a strong degree of hardness to neutron irradiation up to fluence level 1×10^{13} n/cm^2.

The neutron irradiation test is a destructive test. Test procedure follows MIL-STD-883 method 1017 as guidance. The purpose of this test is to determine the device susceptibility to non-ionizing energy loss (NIEL) degradation. Objectives of the test are to detect and measure the degradation of critical device parameters as a function of neutron fluence and to determine if these parameters are within specified limits after exposure to a specified level of neutron fluence.

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Trademarks

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1 Device Information

1.1 Product Description

The TPS7H5030-SP is a radiation-hardness-assured, current mode, single-ended PWM controller with an integrated gate driver that can be utilized in silicon power semiconductor based converter designs. The TPS7H5030 integrates several key functions, such as soft-start, enable, and adjustable slope compensation while maintaining a small package size. The controller also features a 0.6V ± 1% voltage reference tolerance to support highly accurate power converter designs. The TPS7H5030-SP is packaged in a plastic 24-pin HTSSOP PWP package.

1.2 Device Details

Table 1-1 lists the device information and test conditions used in the NDD characterization.

Table 1-1. Device and Exposure Details

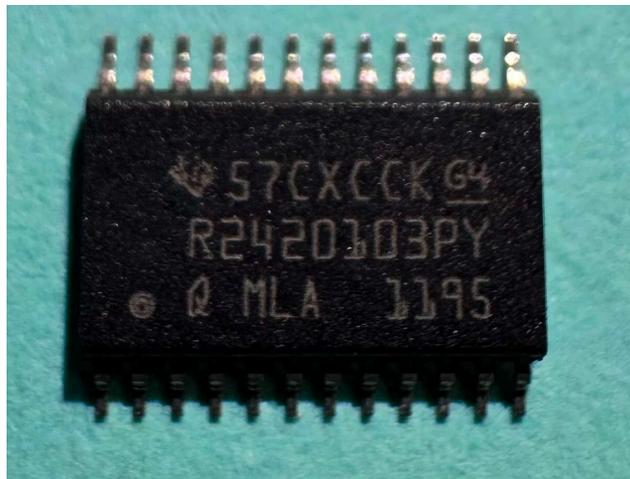| NDD Exposure Details	
TI Device	TPS7H5030-SP
TI Part Name	5962R2420103PYE
Device Function	PWM Controller with Integrated Gate Driver
Package	24-pin HTSSOP-PWP
Technology	LBC7
Wafer Lot Number	4356038
Sample Quantity	12 + 4 control unit
Exposure Facility	VPT
Neutron Fluence (1-MeV equivalent) Level	1×10^{12}, 5×10^{12}, 1×10^{13} n/cm^2
Irradiation Temperature	25°C

Figure 1-1. TPS7H5030-SP Device Used in Exposure

2 Neutron Displacement Test Setup

2.1 Test Overview

General test procedures adhere to MIL-STD-883, Method 1017 as a guide for neutron irradiation. The TPS7H5030-SP was electrically tested using the production automated test equipment (ATE) program at an ambient room temperature of 25°C before and after neutron irradiation.

2.2 Test Facility

VPT Rad performs all neutron displacement damage irradiations in a Low-Enriched, open-pool, water moderated, thermal neutron reactor. VPT Rad uses flat-plate type fuel, and having a maximum thermal energy output of up to 1MW. The Fast Neutron Irradiator (FNI) faces one side of the reactor core, the design produces a geometrical planar beam of fast neutrons that is approximately uniform over an area of 12in × 20in. Lead and thermal neutron absorbing compounds are combined to filter out both fission gammas and thermal neutrons. The ratio of fast-to-thermal neutrons is approximately 400:1, with a gamma exposure of less than 150rad (Si) for a 1E12 n/cm2 (1MeV Si equivalent) exposure. The FNI can accommodate a sample or samples with size up to 30cm in diameter and 15 cm thick including packaging materials. The minimum neutron fluence rate is 1E6 n/cm2-s. The maximum neutron fluence rate is approximately 1.0 E11 n/cm2-s. Both values are 1MeV Si equivalent. The neutron fluence rate is determined using the previously measured neutron radiation field for the FNI, performed in accordance with ASTM standards (ASTM F1190), and correlated to the measured reactor power level. The neutron dose is timed to meet the customer-specified fluence for the irradiation. Neutron

dosimetry meeting ASTM standards (ASTM E265) is used to track and verify irradiations meet the required minimum. The facility retains source-suitability with the Defense Logistics Agency (DLA) Laboratory Suitability Program for ASTM Test Method 1017. The DUTS are typically irradiation in an unbiased condition as per TM1017. If bias conditions are required, the conditions can be maintained through dry thimbles connected to the irradiation volume.

2.3 Test Setup Details

Devices were irradiated at three fluence levels in unbiased conditions: 1×10^{12} n / cm^2, 5×10^{12} n / cm^2 and 1×10^{13} n / cm^2.

Table 2-1. Neutron Irradiation Conditions

Group	Sample Quantity	Neutron Fluence (n / cm^2)	Bias
A	4	1.0×10^{12}	Unbiased
B	4	5.0×10^{12}	Unbiased
C	4	1.0×10^{13}	Unbiased
Control Unit	4	N/A	N/A

3 Test Results

3.1 NDD Characterization Summary

The TPS7H5030-SP has a strong degree of hardness to neutron irradiation up to fluence level 1×10^{13}n/cm2. The measurements taken post-irradiation for each sample set showed a marginal shift for most parameters at each fluence level. The parameters that showed a greater degree of change between pre- and post- irradiation were still within the electrical performance characteristics specified in the Table 3-1.

The results show that all devices were fully functional and within specification limits. A sample size of nine units was exposed for neutron irradiation and an additional unirradiated control unit was used as correlation.

Electrical testing is done for pre- and post- neutron irradiation by ATE electrical test is done at an ambient room temperature of 25°C. Parameters not listed in Table 3-1 are omitted either because there is no parametric data or because verification was done through bench testing.

See Appendix A for NDD test results.

3.2 Data Sheet Electrical Parameters and Associated Tests

Table 3-1. TPS7H5030-SP Data Sheet Electrical Parameters

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT	Test #
SUPPLY VOLTAGES AND CURRENTS								
IDD	Operating supply current	No load for OUT, PVIN = VIN	fSW = 100kHz		6.8	11	mA	14.3, 14.4, 14.16
			fSW = 500kHz		8.5	17		14.5, 14.7, 14.18
		CLOAD = 1000pF for OUT, PVIN = VIN	fSW = 100kHz		8.5	12	mA	14.2
			fSW = 500kHz		14.5	22		14.21
IDD(dis)	Standby current	EN = 0V				8	mA	14.6, 14.8, 14.19
VLDO	Internal linear regulator output voltage (TPS7H503x)	CVLDO = 1µF	8V ≤ VIN ≤ 14V	4.8	5	5.2	V	15.15, 15.16, 15.17
VLDO_DO	Internal linear dropout voltage (TPS7H503x)	IVLDO = 25mA, CVLDO = 1µF				0.5	V	15.19, 15.20, 15.21
ENABLE AND UNDERVOLTAGE LOCKOUT								
VENR	Enable rising threshold			0.57	0.63	0.66	V	16.7, 16.10, 16.17
VENF	Enable falling threshold			0.48	0.52	0.55	V	16.8, 16.11, 16.18
IEN	Enable input leakage current	VIN = 14V	EN = 1V		1	100	nA	16.13, 16.15
			EN = 7V		30	700		16.14, 16.16
PVINUVLOR	PVIN UVLO rising (TPS7H503x)			7.2	7.5	7.8	V	17.13, 17.19
PVINUVLOF	PVIN UVLO falling (TPS7H503x)			6.9	7.2	7.5	V	17.14, 17.20
VINUVLOR	VIN UVLO rising (TPS7H503x)			7.2	7.5	7.8	V	17.16, 17.22
VINUVLOF	VIN UVLO falling (TPS7H503x)			6.9	7.2	7.5	V	17.17, 17.23
VLDOUVLOR	VLDO UVLO rising			3.65	3.77	3.95	V	17.7, 17.10
VLDOUVLOF	VLDO UVLO falling			3.45	3.59	3.75	V	17.8, 17.11
SOFT START								
ISS	Soft-start current	SS = 0.3V		2	2.8	3.4	µA	18.9, 18.13, 18.17, 18.21, 18.25, 18.29
ERROR AMPLIFIER								
EAgm	Error amplifier transconductance	−10µA < ICOMP < 10µA, V(COMP) = 1V		1100	1750	2700	µA/V	19.9, 19.13, 19.39
EAISRC	Error amplifier source current	V(COMP) = 1V, 100mV input overdrive		95		210	µA	19.10, 19.14, 19.40
EAISNK	Error amplifier sink current	V(COMP) = 1V, 100mV input overdrive		95		210	µA	19.11, 19.15, 19.41
EAOS	Error amplifier input offset voltage			−5		6	mV	19.21, 19.24, 19.27, 19.30, 19.46, 19.49
EAIB	Error amplifier input bias current					25	nA	19.12, 19.16, 19.17, 19.18, 19.42, 19.43
OSCILLATOR								
fSYNC	SYNC in frequency range (TPS7H503x)			100		500	kHz	20.28, 20.32, 20.36, 20.38, 20.40, 20.44, 20.48, 20.50, 20.52, 20.54, 20.56, 20.58, 20.98, 20.102
DSYNC	SYNC in duty cycle	Duty cycle of external clock		40%		60%		20.29, 20.30, 20.33, 20.34, 20.41, 20.42, 20.45, 20.46, 20.99,
DTINT	External clock to internal clock detection time	RT populated			2	5	(1/fsw) s	20.84, 20.86, 20.88, 20.90, 20.92, 20.94, 20.120, 20.122, 20.124

Table 3-1. TPS7H5030-SP Data Sheet Electrical Parameters (continued)

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT	Test #
DTEXT	Internal clock to external clock detection time	RT populated			2	5	(1/fsw) s	20.72, 20.74, 20.76, 20.78, 20.80, 20.82, 20.114, 20.116, 20.118
fSW	RT programmed switching frequency	RT = 1.18MΩ		80	95	110	kHz	20.27, 20.31, 20.47, 20.49, 20.97, 20.107
		RT = 560kΩ		175	195	220	kHz	20.35, 20.37, 20.51, 20.53, 20.101, 20.109
		RT = 210kΩ		450	500	550	kHz	20.39, 20.43, 20.55, 20.57, 20.103, 20.111
VOLTAGE REFERENCE								
VREF	Internal voltage reference(2)	Measured at COMP, COMP = VSENSE	TA = 25°C	0.597	0.6	0.603	V	19.19, 19.22, 19.25, 19.28, 19.31, 19.33, 19.35, 19.37, 19.44, 19.47, 19.50, 19.52
REFCAP	REFCAP voltage	CREFCAP = 470nF		1.208	1.223	1.235	V	21.5, 21.7, 21.9, 21.11, 21.13, 21.15, 21.17, 21.19, 21.23, 21.25, 21.27, 21.29
CURRENT SENSE								
CCSR	COMP to CS_ILIM ratio	RSC = open		1.94	2	2.06		28.3, 28.4, 28.15
VCS_ILIM	Current limit (overcurrent) threshold			0.96	1	1.04	V	28.7, 28.8, 28.9, 28.10, 28.17, 28.18
	CS_ILIM to OUT delay	CS_ILIM = 1V to 90% of OUT falling			65	115	ns	28.11, 28.12, 28.13, 28.14, 28.19, 28.20
SLOPE COMPENSATION								
SC	Slope compensation	fSW = 100kHz, RSC = 1.18MΩ			0.029		V/µs	22.25
		fSW = 200kHz, RSC = 562kΩ			0.072		V/µs	22.22, 22.26
		fSW = 500kHz, RSC = 100kΩ			0.306		V/µs	22.23, 22.24, 22.27
GATE DRIVER								
VOL	Low-level voltage	IOL = 50mA			0.08	0.15	V	24.5, 24.7, 24.15
PVIN - VOH	High-level voltage	IOH = 50mA			0.13	0.25	V	24.6, 24.8, 24.16
tR_OUT	OUT rise time (TPS7H503x)	CLOAD = 1000pF, 10% to 90%	VIN = PVIN = 8V		9.5	18	ns	24.17
tR_OUT	OUT rise time	CLOAD = 1000pF, 10% to 90%	VIN = PVIN = 12V		9.5	18	ns	24.9
			VIN = PVIN = 14V		11.5	20		24.11
tF_OUT	OUT fall time (TPS7H503x)	CLOAD = 1000pF, 90% to 10%	VIN = PVIN = 8V		9.5	18	ns	24.18
tF_OUT	OUT fall time	CLOAD = 1000pF, 90% to 10%	VIN = PVIN = 12V		9.5	18	ns	24.1
			VIN = PVIN = 14V		11	18		24.12
ROH	Pull-up resistance	100mA from OUT			2.6	4.7	Ω	23.19, 23.21, 23.23
ROL	Pull-down resistance	100mA into OUT			1.6	2.8	Ω	23.20, 23.22, 23.24
VUCLAMP	Unpowered OUT clamp voltage	Switching disabled	PVIN = 0V		0.7	1	V	24.13
			0V < PVIN < 5V		1.8	2.5		24.14
PWM AND DUTY CYCLE								
ton_min	Minimum on-time				135	165	ns	26.3, 26.4, 26.7
toff_min	Minimum off-time				55	70	ns	26.5, 26.8
DMAX	Maximum duty cycle					100%		27.3, 27.4, 27.5, 27.6, 27.7, 27.8, 27.9, 27.10, 27.11, 27.12, 27.13, 27.14, 27.15, 27.16, 27.17, 27.18, 27.19, 27.20

4 Applicable and Reference Documents

4.1 Applicable Documents

• Texas Instruments, *TPS7H502x-SP/SEP and TPS7H503x-SP/SEP Radiation-Hardened 1MHz Current Mode PWM Controller With Integrated Gate Driver*, data sheet.
• Texas Instruments, *TPS7H5030-SP Evaluation Module*, EVM user's guide.
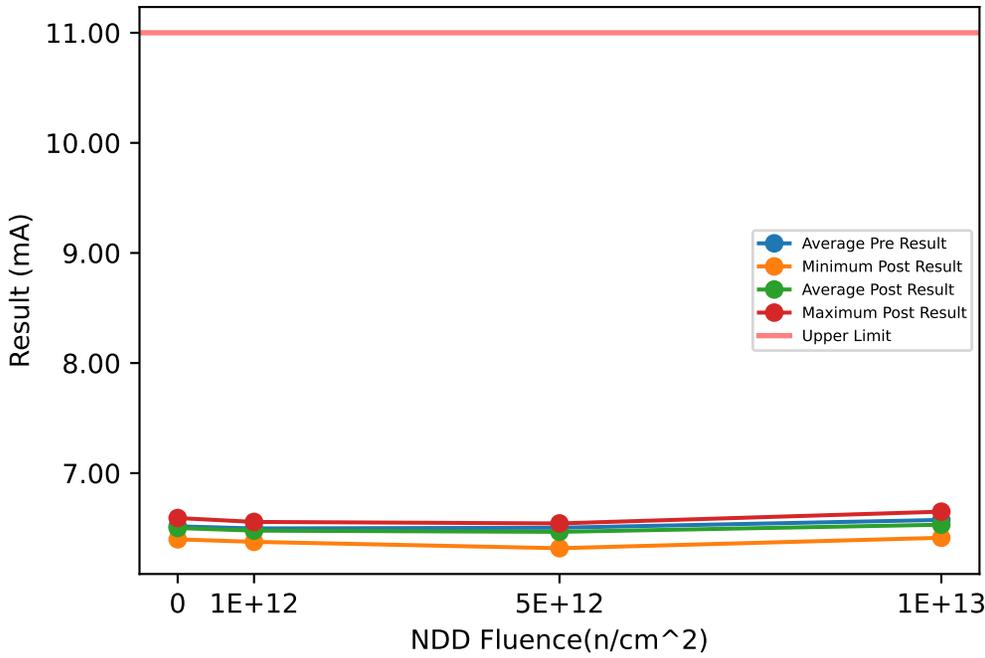
4.2 Reference Documents

Texas Instruments neutron irradiation test follow the guideline from MIL-STD-883 TM 1017. The document is available in Defense Logistic Agency's website.
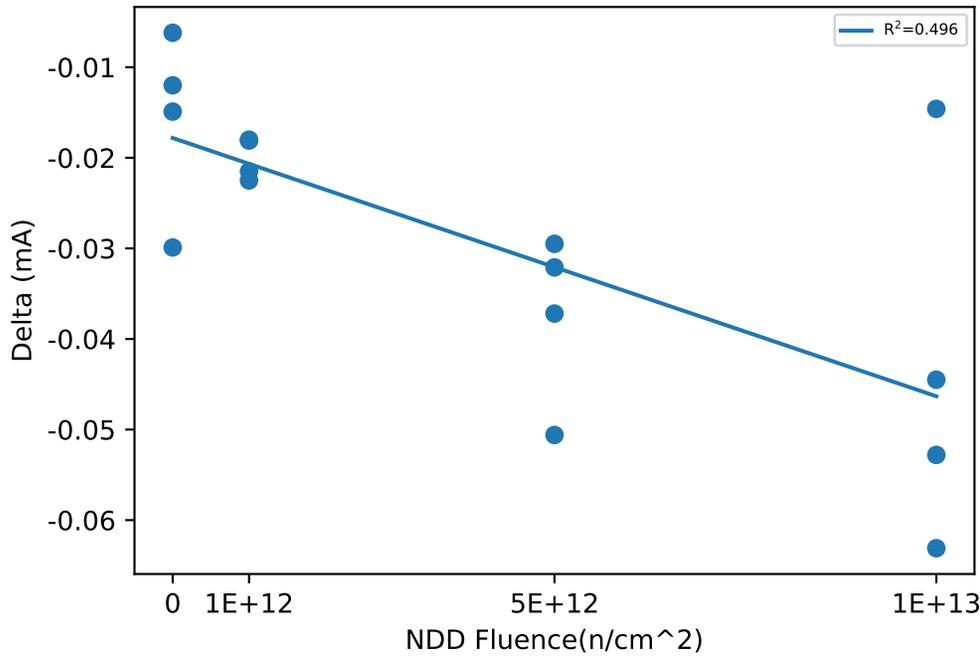
A Appendix: NDD Report Data

This appendix contains the detailed NDD test results.

Device Test: 14.16 IDD|SUPPLY CURRENT/IN/8/8/0/0/5/100kHz//@IDD_ACT_100K_NOLOAD

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 11.0 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	6.5502	6.5277	-0.0225
2	1e+12	NDD	6.5751	6.5571	-0.018
3	1e+12	NDD	6.3976	6.3761	-0.0215
4	1e+12	NDD	6.4686	6.4505	-0.0181
5	5e+12	NDD	6.5616	6.511	-0.0506
6	5e+12	NDD	6.5755	6.5434	-0.0321
7	5e+12	NDD	6.3553	6.3181	-0.0372
8	5e+12	NDD	6.5242	6.4947	-0.0295
9	1e+13	NDD	6.7133	6.6502	-0.0631
10	1e+13	NDD	6.5676	6.5231	-0.0445
11	1e+13	NDD	6.5545	6.5399	-0.0146
12	1e+13	NDD	6.466	6.4132	-0.0528
91	0	CORRELATION	6.4286	6.3987	-0.0299
92	0	CORRELATION	6.452	6.4371	-0.0149
93	0	CORRELATION	6.6045	6.5925	-0.012
94	0	CORRELATION	6.5837	6.5775	-0.0062

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.4286	6.5172	6.6045	0.089712	6.3987	6.5015	6.5925	0.097932	-0.0299	-0.01575	-0.0062	0.010103
1e+12	6.3976	6.4979	6.5751	0.080857	6.3761	6.4779	6.5571	0.081377	-0.0225	-0.020025	-0.018	0.0023171
5e+12	6.3553	6.5042	6.5755	0.10157	6.3181	6.4668	6.5434	0.10118	-0.0506	-0.03735	-0.0295	0.0093945
1e+13	6.466	6.5754	6.7133	0.10244	6.4132	6.5316	6.6502	0.096998	-0.0631	-0.04375	-0.0146	0.02087

Device Test: 14.18 IDD|SUPPLY CURRENT/IN/8/8/0/0/5/500kHz//@IDD_ACT_500K_NOLOAD

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta
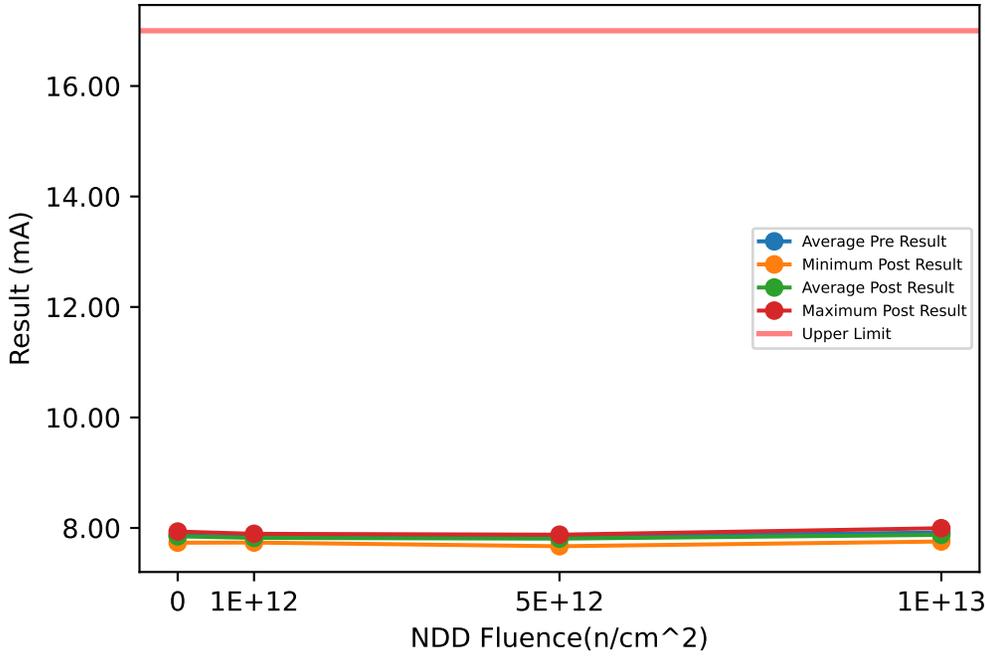

Test Results (Upper Limit = 17.0 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	7.8892	7.8698	-0.0194
2	1e+12	NDD	7.9114	7.8938	-0.0176
3	1e+12	NDD	7.7576	7.7354	-0.0222
4	1e+12	NDD	7.8013	7.779	-0.0223
5	5e+12	NDD	7.8796	7.8367	-0.0429
6	5e+12	NDD	7.9089	7.8781	-0.0308
7	5e+12	NDD	7.7056	7.6691	-0.0365
8	5e+12	NDD	7.8723	7.8412	-0.0311
9	1e+13	NDD	8.0522	7.9953	-0.0569
10	1e+13	NDD	7.9161	7.8723	-0.0438
11	1e+13	NDD	7.8899	7.8765	-0.0134
12	1e+13	NDD	7.8105	7.7548	-0.0557
91	0	CORRELATION	7.758	7.7331	-0.0249
92	0	CORRELATION	7.8114	7.7962	-0.0152
93	0	CORRELATION	7.9477	7.9344	-0.0133
94	0	CORRELATION	7.9404	7.9285	-0.0119
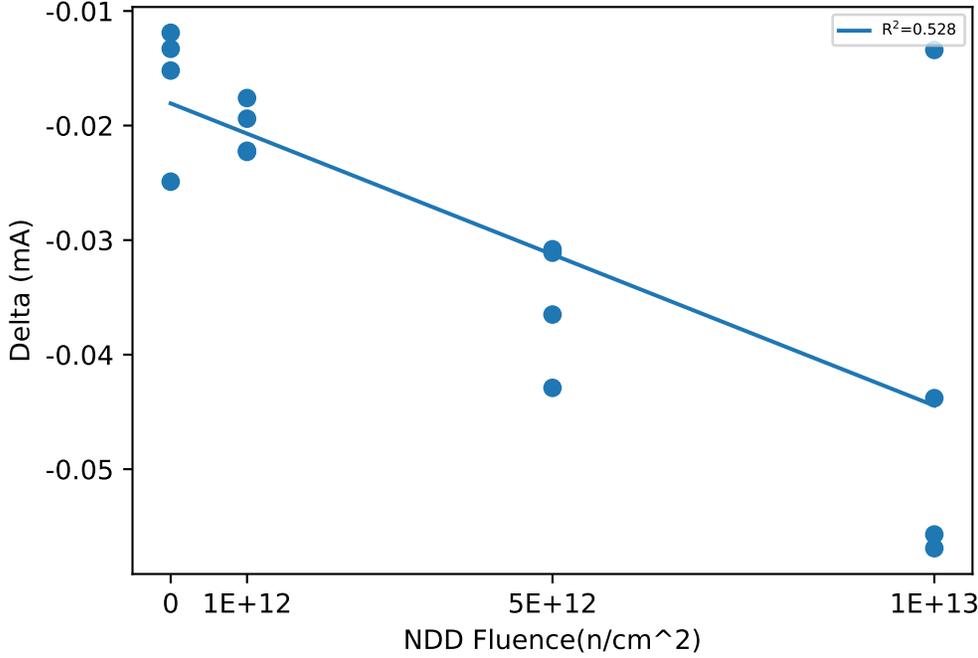
Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.758	7.8644	7.9477	0.094595	7.7331	7.848	7.9344	0.099717	-0.0249	-0.016325	-0.0119	0.0058745
1e+12	7.7576	7.8399	7.9114	0.072586	7.7354	7.8195	7.8938	0.074752	-0.0223	-0.020375	-0.0176	0.0022867
5e+12	7.7056	7.8416	7.9089	0.092036	7.6691	7.8063	7.8781	0.093312	-0.0429	-0.035325	-0.0308	0.0056888
1e+13	7.8105	7.9172	8.0522	0.10059	7.7548	7.8747	7.9953	0.098199	-0.0569	-0.04245	-0.0134	0.020249

Device Test: 14.19 IDD_DIS|STANDBY CURRENT/IN/8/8/0/0/5/500kHz//@IDD_DIS

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 8.0 (mA))

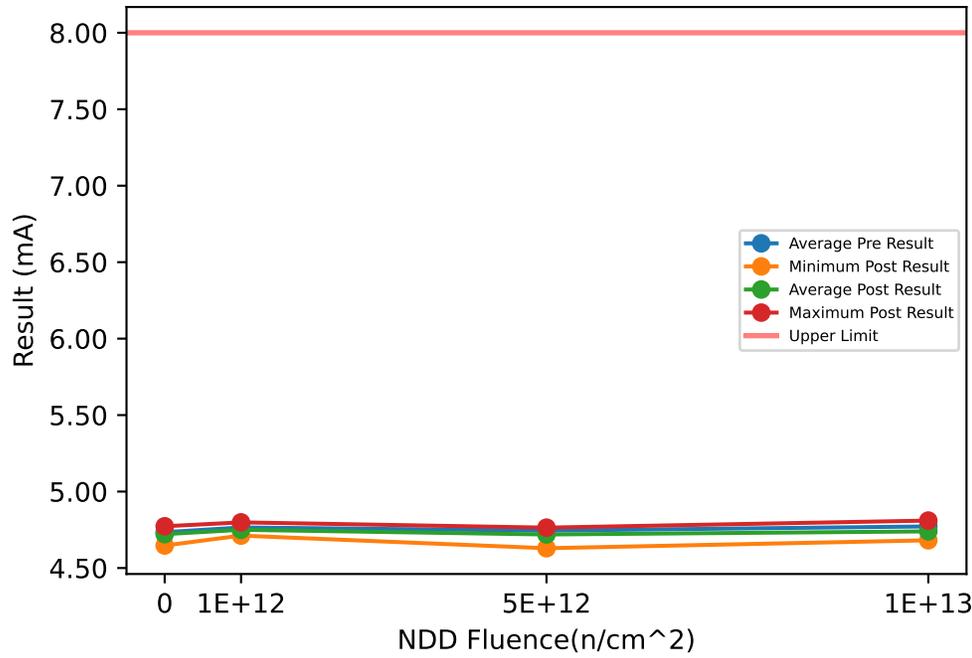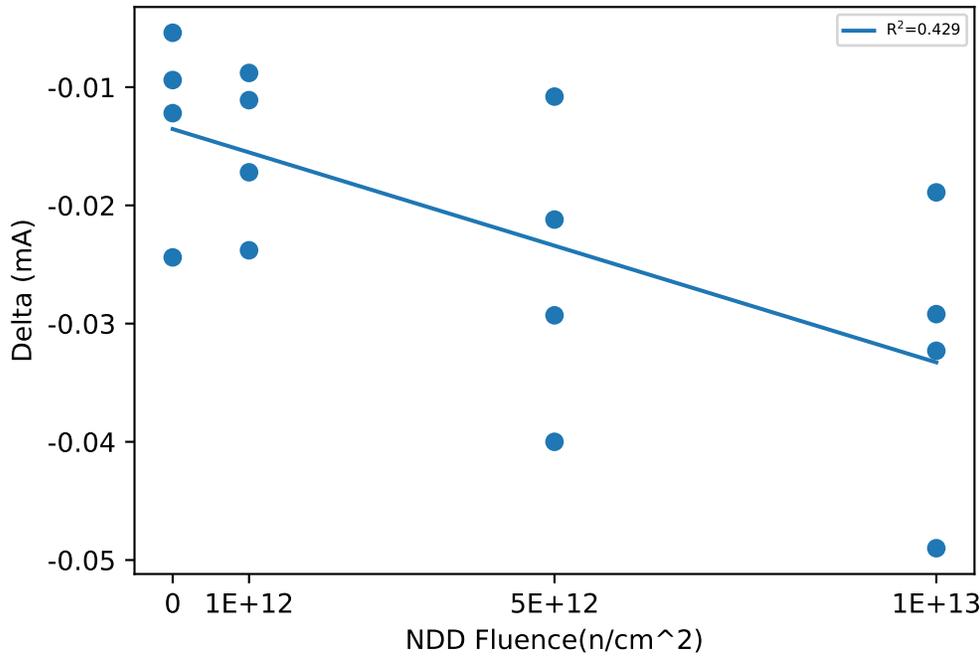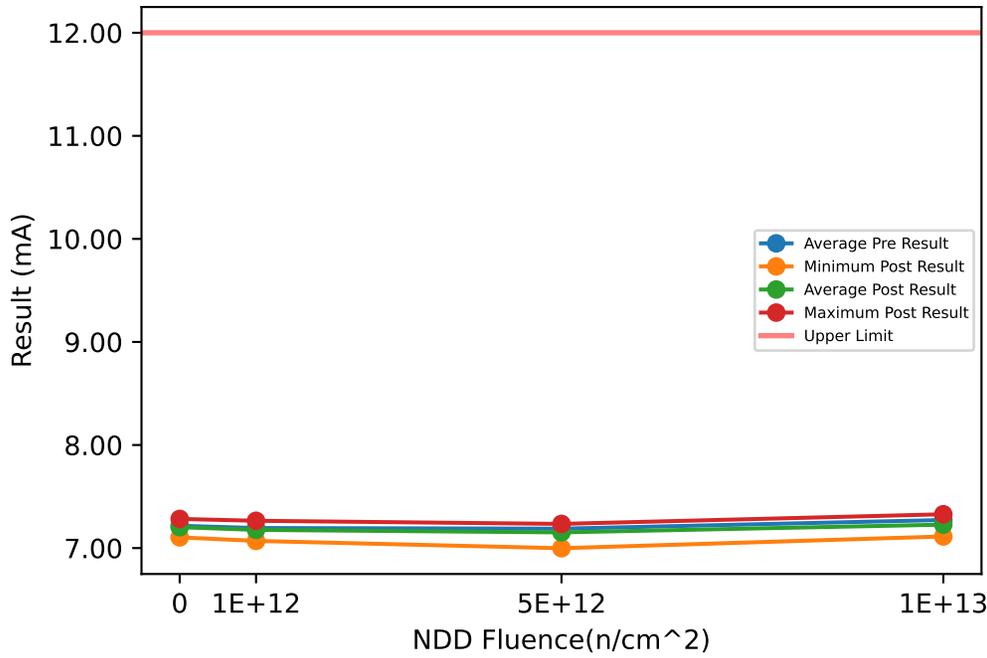| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	4.7712	4.7474	-0.0238
2	1e+12	NDD	4.8097	4.7986	-0.0111
3	1e+12	NDD	4.7293	4.7121	-0.0172
4	1e+12	NDD	4.7503	4.7415	-0.0088
5	5e+12	NDD	4.787	4.747	-0.04
6	5e+12	NDD	4.7853	4.7641	-0.0212
7	5e+12	NDD	4.6588	4.6295	-0.0293
8	5e+12	NDD	4.7477	4.7369	-0.0108
9	1e+13	NDD	4.8593	4.8103	-0.049
10	1e+13	NDD	4.764	4.7348	-0.0292
11	1e+13	NDD	4.7507	4.7318	-0.0189
12	1e+13	NDD	4.7136	4.6813	-0.0323
91	0	CORRELATION	4.6717	4.6473	-0.0244
92	0	CORRELATION	4.7399	4.7305	-0.0094
93	0	CORRELATION	4.7852	4.773	-0.0122
94	0	CORRELATION	4.7405	4.7351	-0.0054

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.6717	4.7343	4.7852	0.046831	4.6473	4.7215	4.773	0.05299	-0.0244	-0.01285	-0.0054	0.00819
1e+12	4.7293	4.7651	4.8097	0.034288	4.7121	4.7499	4.7986	0.035951	-0.0238	-0.015225	-0.0088	0.0067263
5e+12	4.6588	4.7447	4.787	0.060071	4.6295	4.7194	4.7641	0.060959	-0.04	-0.025325	-0.0108	0.012371
1e+13	4.7136	4.7719	4.8593	0.062047	4.6813	4.7395	4.8103	0.05317	-0.049	-0.03235	-0.0189	0.012491

# Device Test: 14.20 IDD|SUPPLY CURRENT/IN/8/8/0/1000/5/100kHz//@IDD_ACT_100K_LOAD

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 12.0 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	7.2434	7.2236	-0.0198
2	1e+12	NDD	7.2798	7.2648	-0.015
3	1e+12	NDD	7.0911	7.0695	-0.0216
4	1e+12	NDD	7.1639	7.1474	-0.0165
5	5e+12	NDD	7.2352	7.1878	-0.0474
6	5e+12	NDD	7.2662	7.2345	-0.0317
7	5e+12	NDD	7.0354	6.9985	-0.0369
8	5e+12	NDD	7.2151	7.1881	-0.027
9	1e+13	NDD	7.3904	7.328	-0.0624
10	1e+13	NDD	7.2733	7.2247	-0.0486
11	1e+13	NDD	7.2586	7.2435	-0.0151
12	1e+13	NDD	7.1675	7.1127	-0.0548
91	0	CORRELATION	7.1312	7.104	-0.0272
92	0	CORRELATION	7.1564	7.1439	-0.0125
93	0	CORRELATION	7.2935	7.283	-0.0105
94	0	CORRELATION	7.2847	7.2795	-0.0052
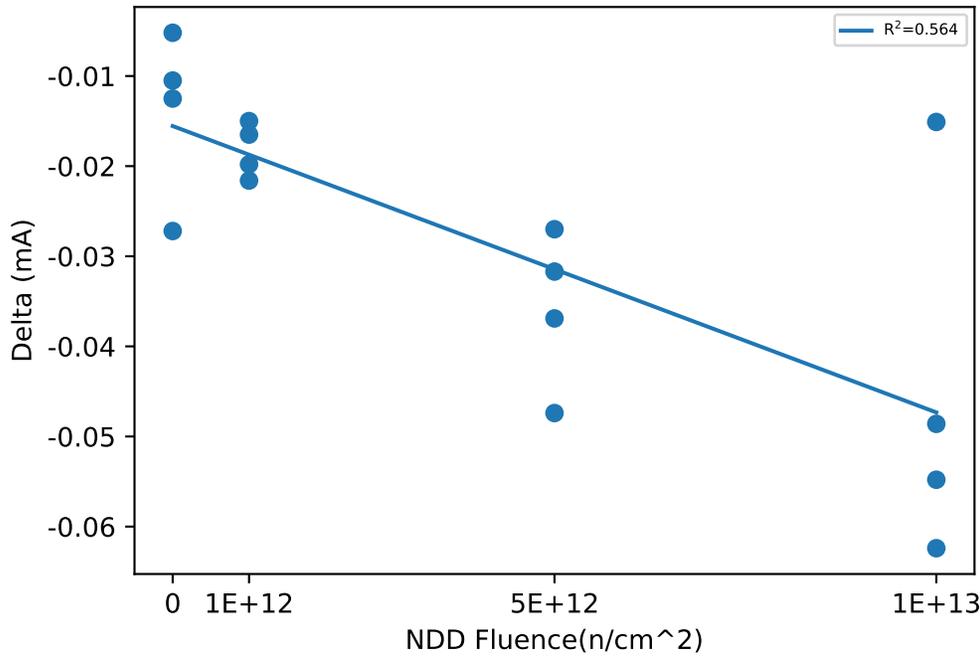
Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.1312	7.2165	7.2935	0.084594	7.104	7.2026	7.283	0.092278	-0.0272	-0.01385	-0.0052	0.0094179
1e+12	7.0911	7.1945	7.2798	0.084252	7.0695	7.1763	7.2648	0.086238	-0.0216	-0.018225	-0.015	0.0030137
5e+12	7.0354	7.188	7.2662	0.10387	6.9985	7.1522	7.2345	0.10481	-0.0474	-0.03575	-0.027	0.0087561
1e+13	7.1675	7.2725	7.3904	0.091505	7.1127	7.2272	7.328	0.088587	-0.0624	-0.045225	-0.0151	0.020861

Device Test: 14.21 IDD|SUPPLY CURRENT/IN/8/8/0/1000/5/500kHz//@IDD_ACT_500K_LOAD

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 22.0 (mA))

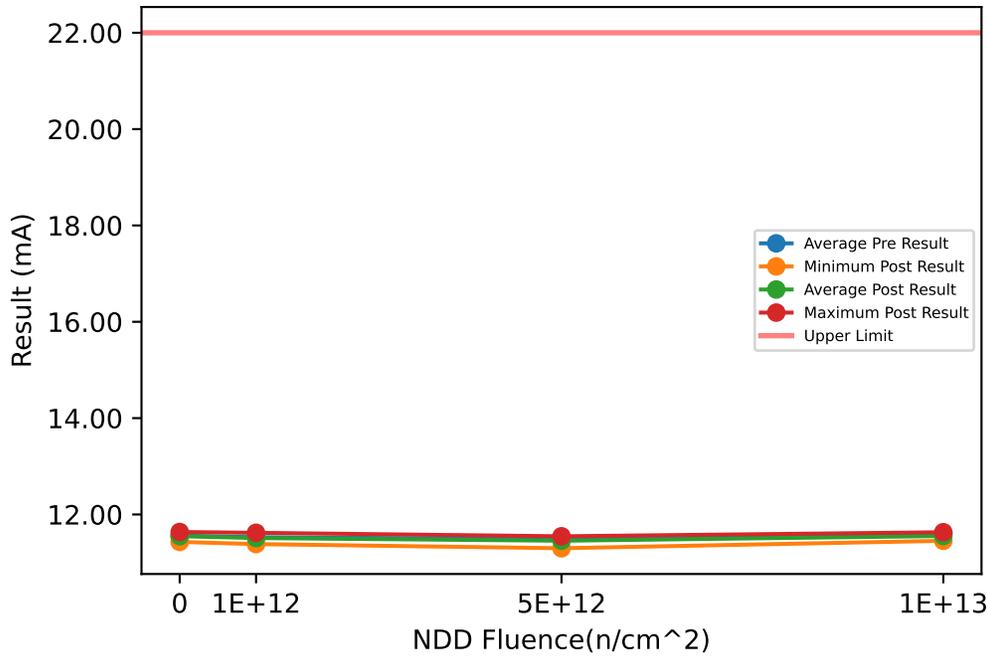| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	11.59	11.576	-0.0142
2	1e+12	NDD	11.633	11.619	-0.0136
3	1e+12	NDD	11.408	11.385	-0.0226
4	1e+12	NDD	11.48	11.461	-0.0193
5	5e+12	NDD	11.494	11.455	-0.0384
6	5e+12	NDD	11.577	11.547	-0.0305
7	5e+12	NDD	11.336	11.299	-0.0373
8	5e+12	NDD	11.545	11.518	-0.0267
9	1e+13	NDD	11.695	11.631	-0.0639
10	1e+13	NDD	11.622	11.566	-0.0564
11	1e+13	NDD	11.583	11.56	-0.0232
12	1e+13	NDD	11.517	11.453	-0.0634
91	0	CORRELATION	11.45	11.431	-0.0198
92	0	CORRELATION	11.529	11.519	-0.0102
93	0	CORRELATION	11.621	11.61	-0.0112
94	0	CORRELATION	11.643	11.636	-0.0068
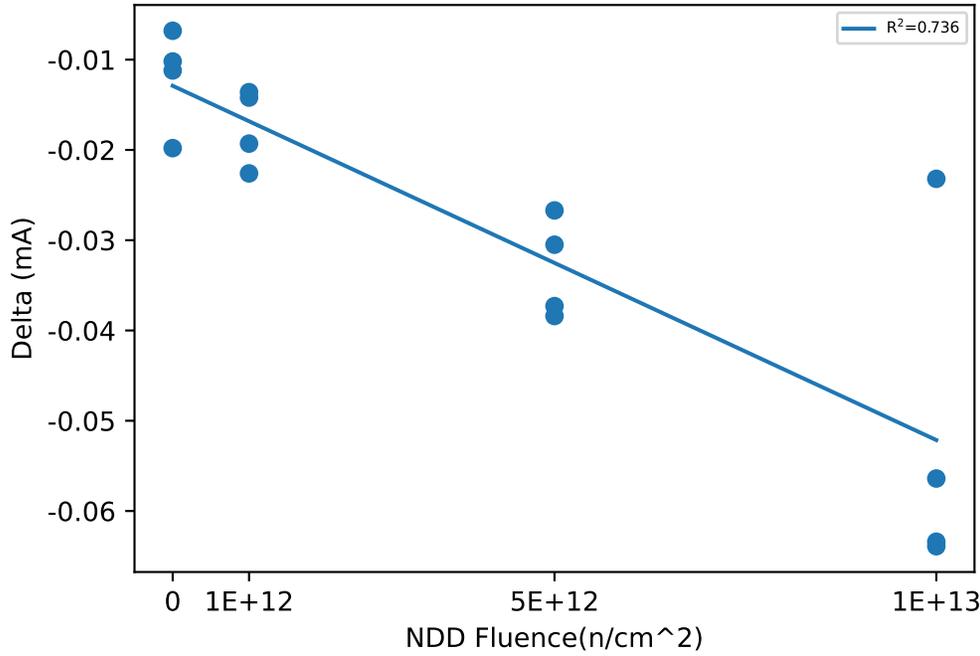
Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	11.45	11.561	11.643	0.088638	11.431	11.549	11.636	0.093487	-0.0198	-0.012	-0.0068	0.0055305
1e+12	11.408	11.528	11.633	0.10247	11.385	11.51	11.619	0.10674	-0.0226	-0.017425	-0.0136	0.0042945
5e+12	11.336	11.488	11.577	0.10679	11.299	11.455	11.547	0.11062	-0.0384	-0.033225	-0.0267	0.0055794
1e+13	11.517	11.604	11.695	0.074565	11.453	11.553	11.631	0.073641	-0.0639	-0.051725	-0.0232	0.019322

Device Test: 14.3 IDD|SUPPLY CURRENT/IN/12/12/0/0/5/100kHz//@IDD_ACT_100K_NOLOAD

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 11.0 (mA))

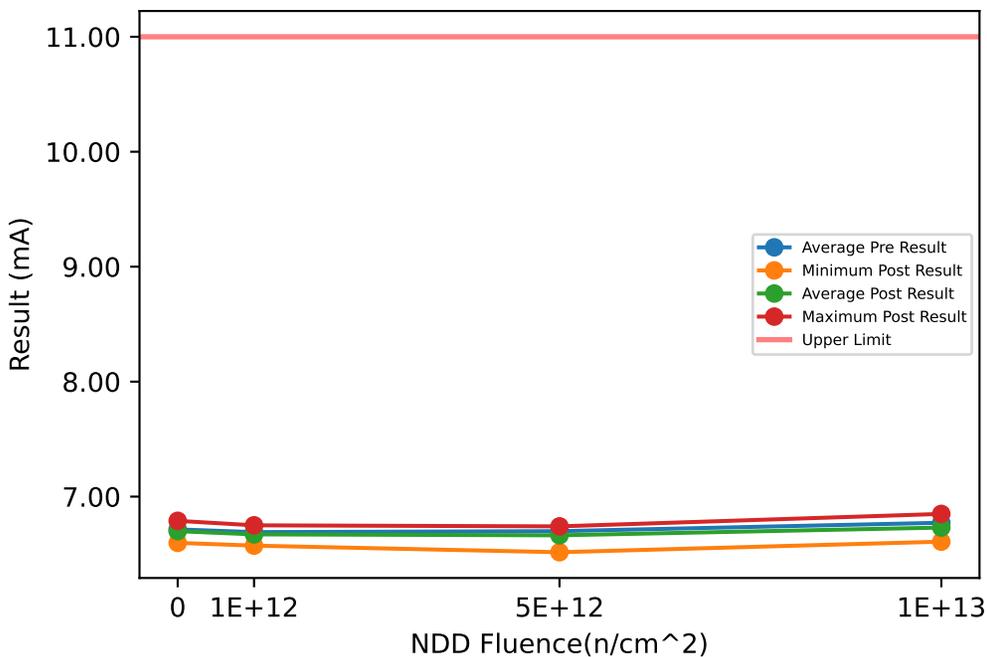| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	6.7385	6.7249	-0.0136
2	1e+12	NDD	6.7673	6.7502	-0.0171
3	1e+12	NDD	6.5965	6.5736	-0.0229
4	1e+12	NDD	6.6621	6.6369	-0.0252
5	5e+12	NDD	6.7463	6.7059	-0.0404
6	5e+12	NDD	6.7723	6.7411	-0.0312
7	5e+12	NDD	6.5541	6.5162	-0.0379
8	5e+12	NDD	6.725	6.6899	-0.0351
9	1e+13	NDD	6.9025	6.8495	-0.053
10	1e+13	NDD	6.7691	6.7266	-0.0425
11	1e+13	NDD	6.7514	6.7379	-0.0135
12	1e+13	NDD	6.6673	6.6082	-0.0591
91	0	CORRELATION	6.6184	6.5978	-0.0206
92	0	CORRELATION	6.6472	6.6328	-0.0144
93	0	CORRELATION	6.803	6.7893	-0.0137
94	0	CORRELATION	6.7909	6.7775	-0.0134
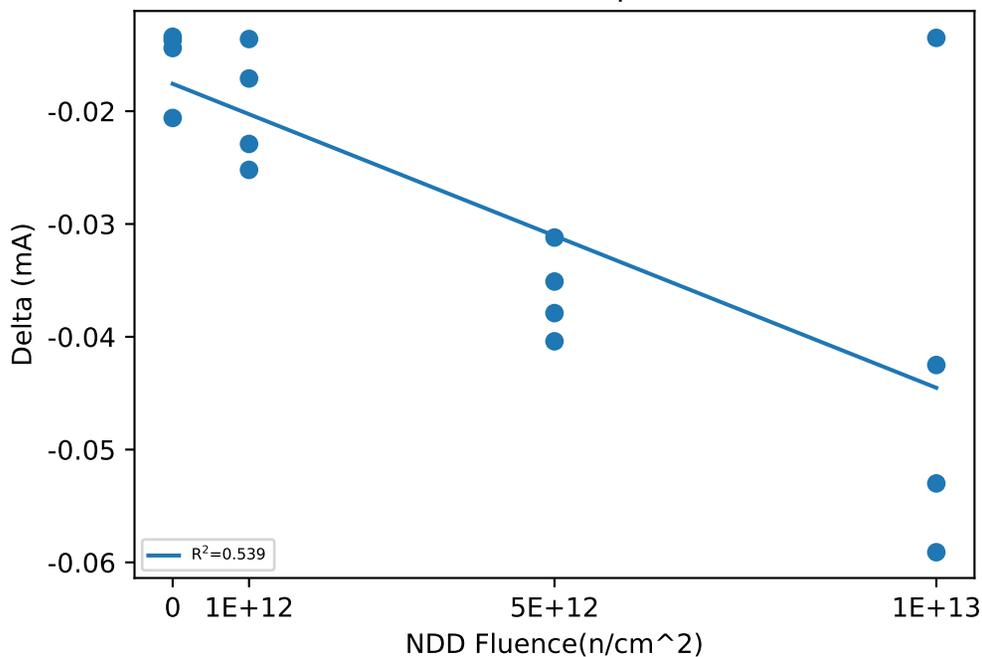
Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.6184	6.7149	6.803	0.095626	6.5978	6.6993	6.7893	0.098217	-0.0206	-0.015525	-0.0134	0.0034092
1e+12	6.5965	6.6911	6.7673	0.077122	6.5736	6.6714	6.7502	0.081295	-0.0252	-0.0197	-0.0136	0.005306
5e+12	6.5541	6.6994	6.7723	0.098795	6.5162	6.6633	6.7411	0.10036	-0.0404	-0.03615	-0.0312	0.0039467
1e+13	6.6673	6.7726	6.9025	0.097338	6.6082	6.7306	6.8495	0.098638	-0.0591	-0.042025	-0.0135	0.020215
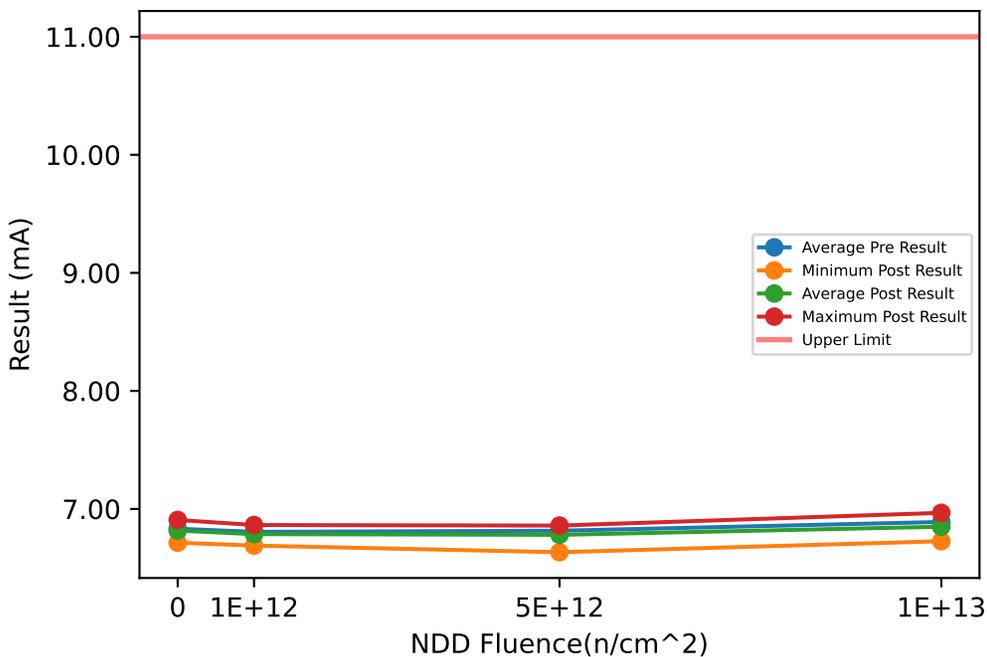
Device Test: 14.4 IDD|SUPPLY CURRENT/IN/14/14/0/0/5/100kHz//@IDD_ACT_100K_NOLOAD

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

R²=0.519

Test Results (Upper Limit = 11.0 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	6.8551	6.842	-0.0131
2	1e+12	NDD	6.8814	6.8638	-0.0176
3	1e+12	NDD	6.7121	6.6896	-0.0225
4	1e+12	NDD	6.7755	6.7501	-0.0254
5	5e+12	NDD	6.8607	6.8215	-0.0392
6	5e+12	NDD	6.888	6.859	-0.029
7	5e+12	NDD	6.6704	6.6333	-0.0371
8	5e+12	NDD	6.8421	6.8081	-0.034
9	1e+13	NDD	7.0174	6.967	-0.0504
10	1e+13	NDD	6.8888	6.8473	-0.0415
11	1e+13	NDD	6.8681	6.8555	-0.0126
12	1e+13	NDD	6.7846	6.7266	-0.058
91	0	CORRELATION	6.7346	6.7141	-0.0205
92	0	CORRELATION	6.7619	6.7472	-0.0147
93	0	CORRELATION	6.9201	6.9067	-0.0134
94	0	CORRELATION	6.9118	6.8985	-0.0133

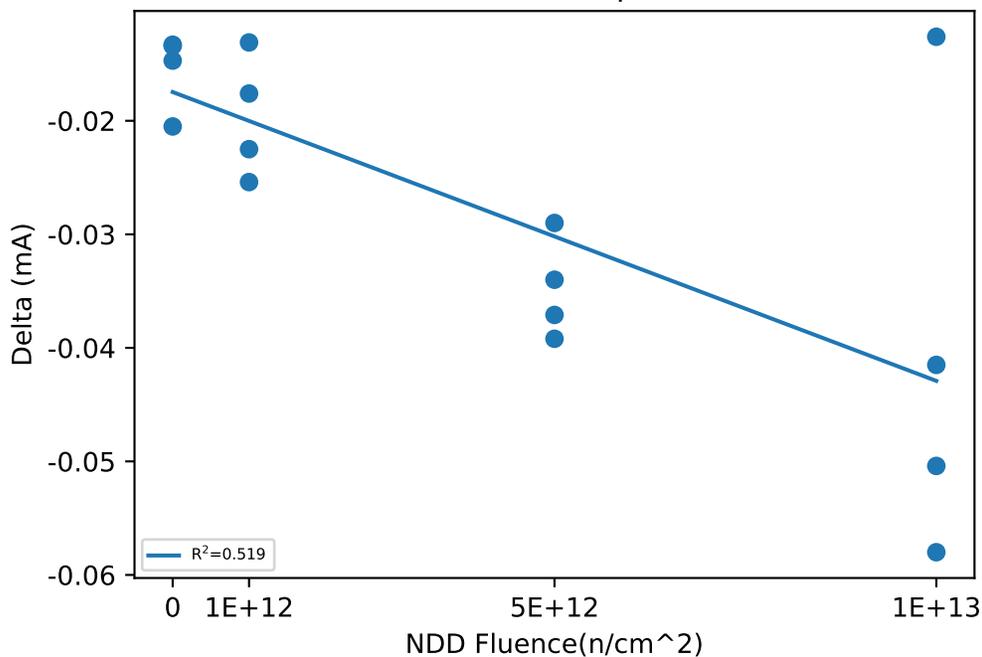## Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.7346	6.8321	6.9201	0.09752	6.7141	6.8166	6.9067	0.10025	-0.0205	-0.015475	-0.0133	0.0034102
1e+12	6.7121	6.806	6.8814	0.077122	6.6896	6.7864	6.8638	0.081179	-0.0254	-0.01965	-0.0131	0.0054249
5e+12	6.6704	6.8153	6.888	0.098422	6.6333	6.7805	6.859	0.10045	-0.0392	-0.034825	-0.029	0.004432
1e+13	6.7846	6.8897	7.0174	0.096299	6.7266	6.8491	6.967	0.098236	-0.058	-0.040625	-0.0126	0.019863

Device Test: 14.5 IDD|SUPPLY CURRENT/IN/12/12/0/0/5/500kHz//@IDD_ACT_500K_NOLOAD
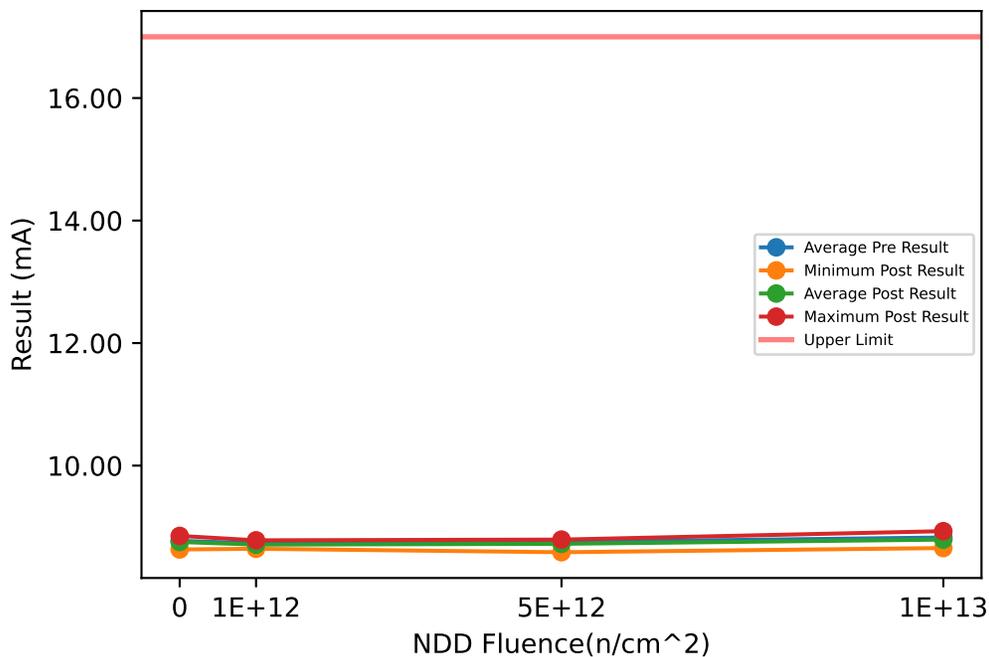
NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 17.0 (mA))

| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	8.7869	8.7807	-0.0062
2	1e+12	NDD	8.7846	8.7678	-0.0168
3	1e+12	NDD	8.6753	8.65	-0.0253
4	1e+12	NDD	8.6806	8.6427	-0.0379
5	5e+12	NDD	8.7821	8.7609	-0.0212
6	5e+12	NDD	8.8159	8.7924	-0.0235
7	5e+12	NDD	8.6191	8.5863	-0.0328
8	5e+12	NDD	8.7924	8.7537	-0.0387
9	1e+13	NDD	8.9635	8.93	-0.0335
10	1e+13	NDD	8.8336	8.8002	-0.0334
11	1e+13	NDD	8.7905	8.784	-0.0065
12	1e+13	NDD	8.7193	8.6546	-0.0647
91	0	CORRELATION	8.6442	8.6316	-0.0126
92	0	CORRELATION	8.6973	8.6809	-0.0164
93	0	CORRELATION	8.8662	8.8489	-0.0173
94	0	CORRELATION	8.8805	8.8526	-0.0279
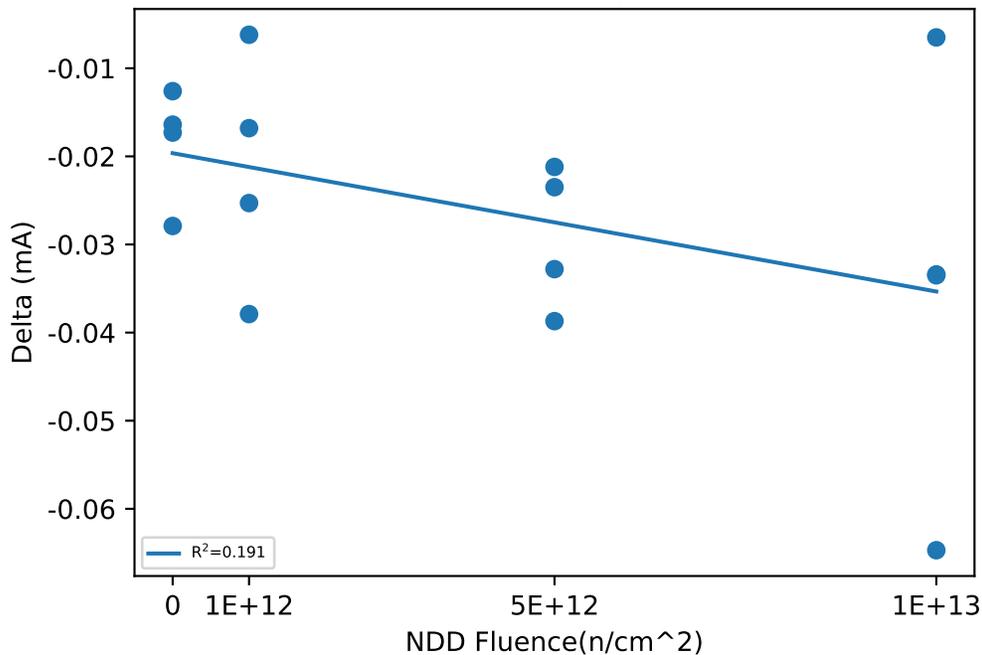
Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.6442	8.7721	8.8805	0.11911	8.6316	8.7535	8.8526	0.11409	-0.0279	-0.01855	-0.0126	0.0065577
1e+12	8.6753	8.7318	8.7869	0.062283	8.6427	8.7103	8.7807	0.074091	-0.0379	-0.02155	-0.0062	0.013411
5e+12	8.6191	8.7524	8.8159	0.089969	8.5863	8.7233	8.7924	0.092883	-0.0387	-0.02905	-0.0212	0.008157
1e+13	8.7193	8.8267	8.9635	0.10264	8.6546	8.7922	8.93	0.11263	-0.0647	-0.034525	-0.0065	0.023792

Device Test: 14.6 IDD_DIS|STANDBY CURRENT/IN/12/12/0/0/5/500kHz//@IDD_DIS

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 8.0 (mA))

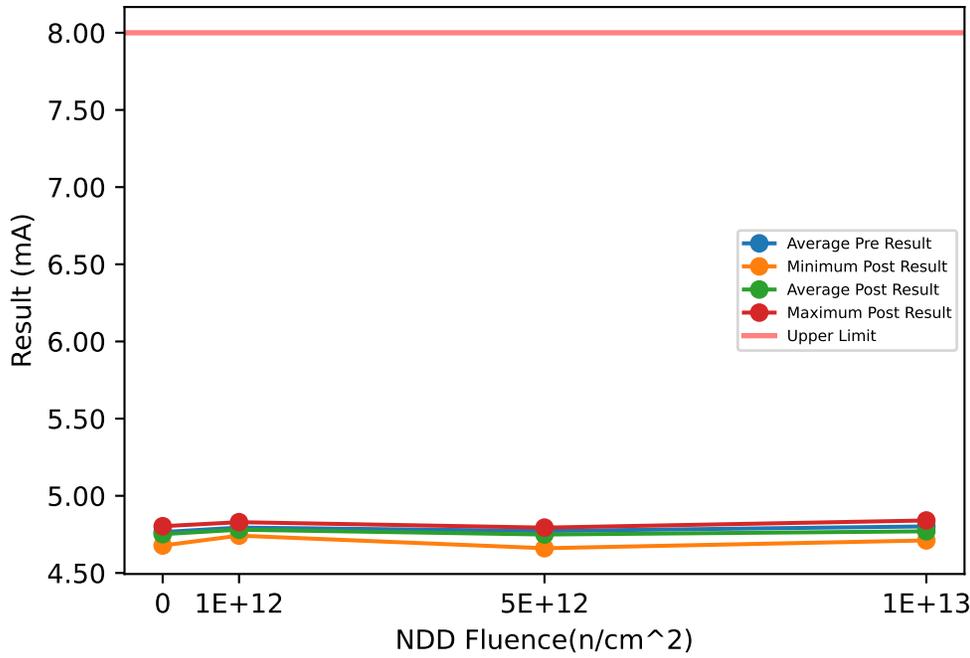| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	4.7948	4.7812	-0.0136
2	1e+12	NDD	4.8421	4.8292	-0.0129
3	1e+12	NDD	4.7569	4.742	-0.0149
4	1e+12	NDD	4.7828	4.7688	-0.014
5	5e+12	NDD	4.8052	4.7777	-0.0275
6	5e+12	NDD	4.8139	4.7939	-0.02
7	5e+12	NDD	4.6904	4.6604	-0.03
8	5e+12	NDD	4.7793	4.7645	-0.0148
9	1e+13	NDD	4.8822	4.8402	-0.042
10	1e+13	NDD	4.7951	4.7664	-0.0287
11	1e+13	NDD	4.7812	4.7618	-0.0194
12	1e+13	NDD	4.7481	4.711	-0.0371
91	0	CORRELATION	4.6971	4.678	-0.0191
92	0	CORRELATION	4.7718	4.7604	-0.0114
93	0	CORRELATION	4.8159	4.803	-0.0129
94	0	CORRELATION	4.7757	4.7645	-0.0112
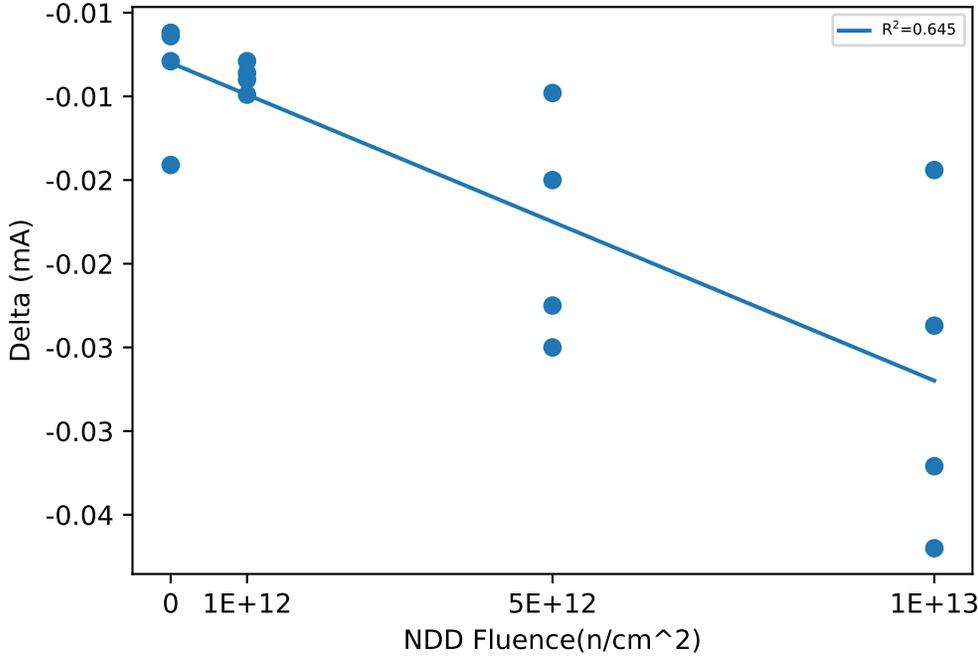
Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.6971	4.7651	4.8159	0.049537	4.678	4.7515	4.803	0.052608	-0.0191	-0.01365	-0.0112	0.0037117
1e+12	4.7569	4.7942	4.8421	0.035665	4.742	4.7803	4.8292	0.036474	-0.0149	-0.01385	-0.0129	0.00083467
5e+12	4.6904	4.7722	4.8139	0.056479	4.6604	4.7491	4.7939	0.06036	-0.03	-0.023075	-0.0148	0.0069634
1e+13	4.7481	4.8017	4.8822	0.057204	4.711	4.7698	4.8402	0.053195	-0.042	-0.0318	-0.0194	0.0099247

Device Test: 14.7 IDD|SUPPLY CURRENT/IN/14/14/0/0/5/500kHz//@IDD_ACT_500K_NOLOAD

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 17.0 (mA))

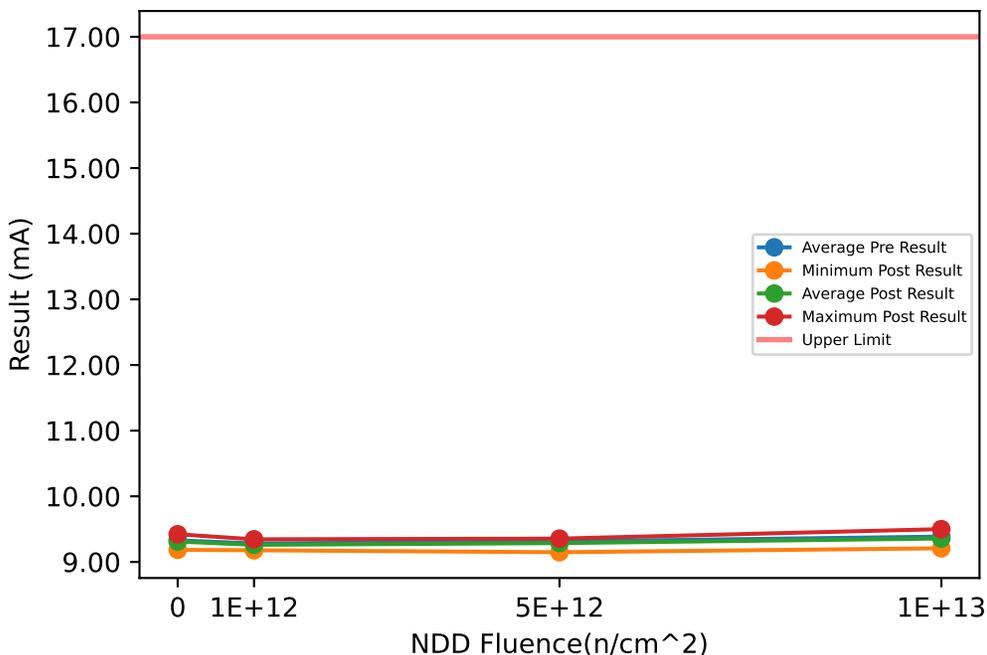| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	9.3471	9.3444	-0.0027
2	1e+12	NDD	9.3228	9.309	-0.0138
3	1e+12	NDD	9.2348	9.2096	-0.0252
4	1e+12	NDD	9.2197	9.1777	-0.042
5	5e+12	NDD	9.3427	9.3284	-0.0143
6	5e+12	NDD	9.3738	9.3552	-0.0186
7	5e+12	NDD	9.1771	9.1479	-0.0292
8	5e+12	NDD	9.3536	9.3156	-0.038
9	1e+13	NDD	9.5262	9.4996	-0.0266
10	1e+13	NDD	9.4004	9.3743	-0.0261
11	1e+13	NDD	9.3449	9.3441	-0.0008
12	1e+13	NDD	9.2717	9.2078	-0.0639
91	0	CORRELATION	9.1945	9.1844	-0.0101
92	0	CORRELATION	9.2387	9.2233	-0.0154
93	0	CORRELATION	9.4322	9.4135	-0.0187
94	0	CORRELATION	9.4517	9.4213	-0.0304
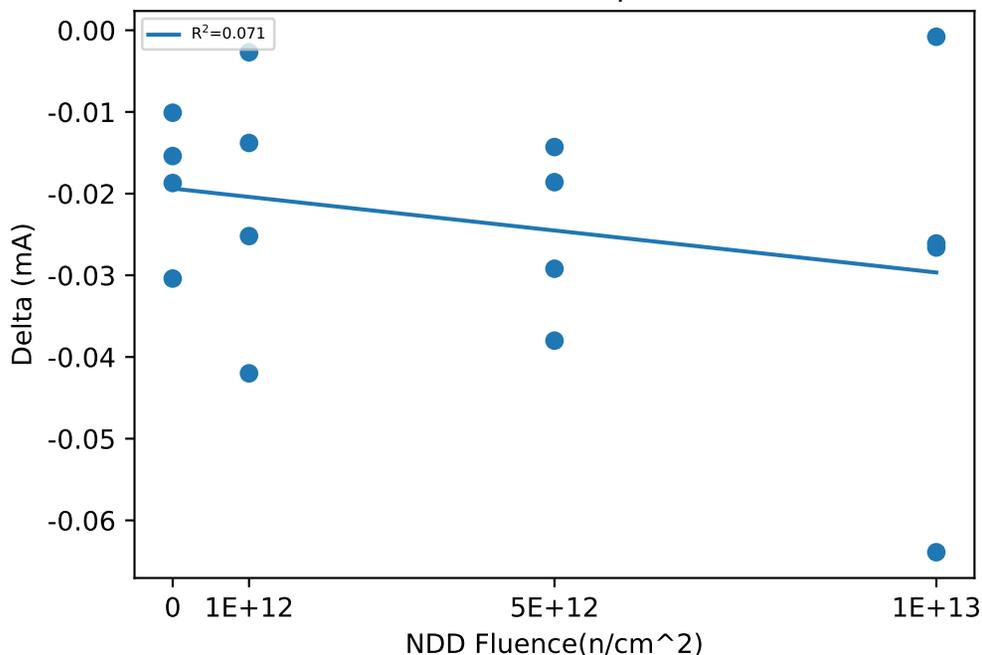
Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.1945	9.3293	9.4517	0.13159	9.1844	9.3106	9.4213	0.12435	-0.0304	-0.01865	-0.0101	0.0085971
1e+12	9.2197	9.2811	9.3471	0.063268	9.1777	9.2602	9.3444	0.079242	-0.042	-0.020925	-0.0027	0.016786
5e+12	9.1771	9.3118	9.3738	0.09072	9.1479	9.2868	9.3552	0.094042	-0.038	-0.025025	-0.0143	0.010678
1e+13	9.2717	9.3858	9.5262	0.10742	9.2078	9.3564	9.4996	0.11981	-0.0639	-0.02935	-0.0008	0.025993

Device Test: 14.8 IDD_DIS|STANDBY CURRENT/IN/14/14/0/0/5/500kHz//@IDD_DIS

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 8.0 (mA))

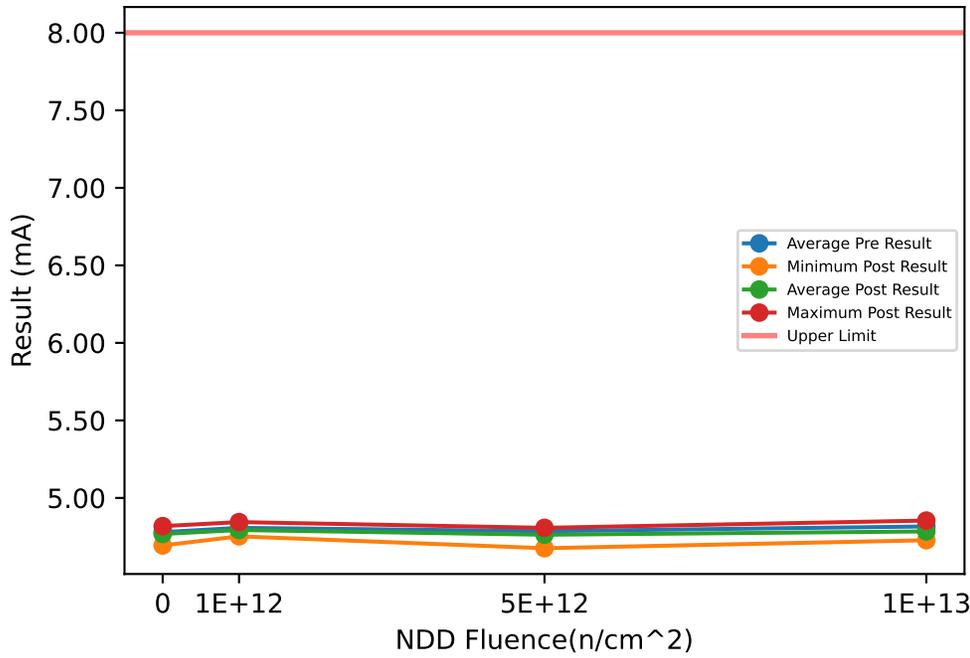| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	4.808	4.7932	-0.0148
2	1e+12	NDD	4.8549	4.8442	-0.0107
3	1e+12	NDD	4.7689	4.7524	-0.0165
4	1e+12	NDD	4.7964	4.7824	-0.014
5	5e+12	NDD	4.8179	4.7885	-0.0294
6	5e+12	NDD	4.8269	4.8072	-0.0197
7	5e+12	NDD	4.7054	4.6757	-0.0297
8	5e+12	NDD	4.7933	4.7791	-0.0142
9	1e+13	NDD	4.8958	4.854	-0.0418
10	1e+13	NDD	4.8083	4.7802	-0.0281
11	1e+13	NDD	4.7948	4.7744	-0.0204
12	1e+13	NDD	4.7647	4.7272	-0.0375
91	0	CORRELATION	4.7119	4.6935	-0.0184
92	0	CORRELATION	4.7859	4.7775	-0.0084
93	0	CORRELATION	4.8293	4.8181	-0.0112
94	0	CORRELATION	4.7909	4.7809	-0.01
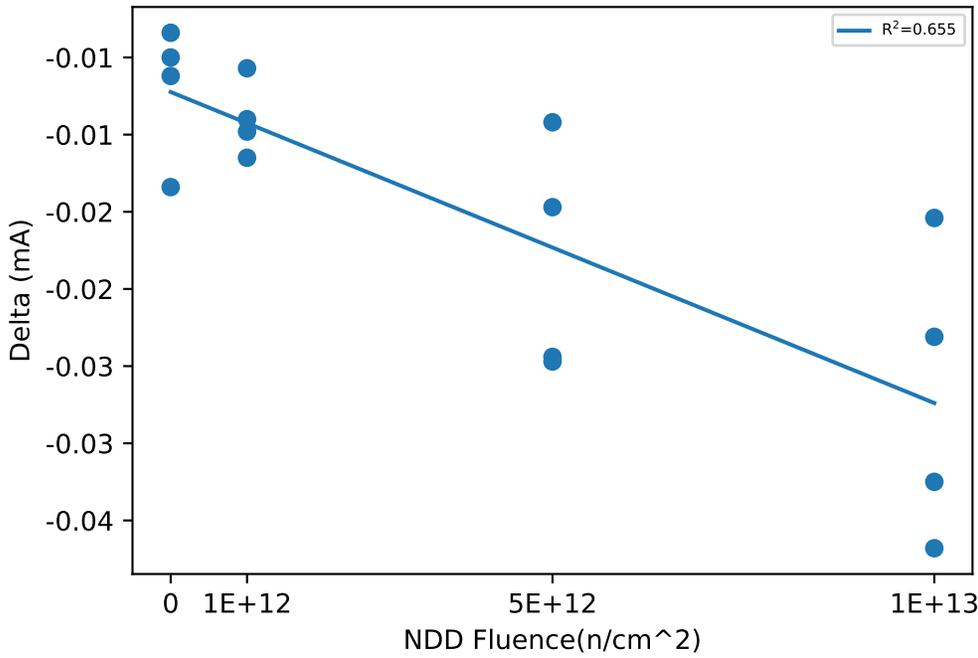
Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.7119	4.7795	4.8293	0.04906	4.6935	4.7675	4.8181	0.05265	-0.0184	-0.012	-0.0084	0.0044181
1e+12	4.7689	4.8071	4.8549	0.035867	4.7524	4.7931	4.8442	0.038219	-0.0165	-0.014	-0.0107	0.0024345
5e+12	4.7054	4.7859	4.8269	0.055498	4.6757	4.7626	4.8072	0.059115	-0.0297	-0.02325	-0.0142	0.0076142
1e+13	4.7647	4.8159	4.8958	0.056298	4.7272	4.7839	4.854	0.052386	-0.0418	-0.03195	-0.0204	0.0095925

Device Test: 15.15 VLDO|V_VLDO/VLDO/8/8/0/0/5/500kHz//@V_LDO_INT

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 4.8, Upper Limit = 5.2 (V))

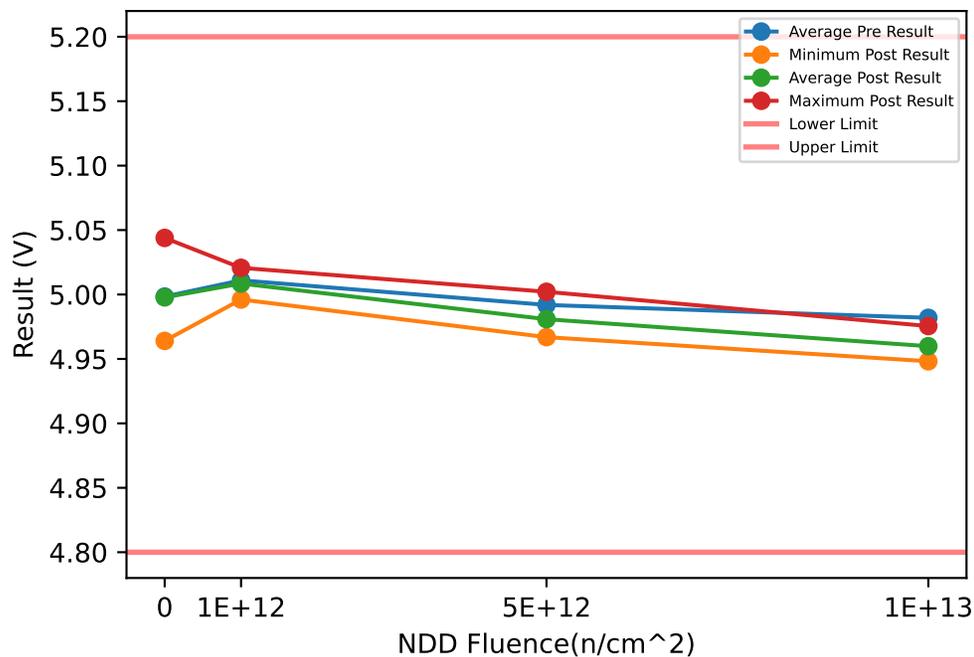| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	4.9985	4.9961	-0.0024
2	1e+12	NDD	5.0161	5.0131	-0.003
3	1e+12	NDD	5.006	5.004	-0.002
4	1e+12	NDD	5.0234	5.0207	-0.0027
5	5e+12	NDD	4.9821	4.9705	-0.0116
6	5e+12	NDD	5.014	5.0021	-0.0119
7	5e+12	NDD	4.9763	4.9669	-0.0094
8	5e+12	NDD	4.9952	4.9838	-0.0114
9	1e+13	NDD	4.9703	4.9482	-0.0221
10	1e+13	NDD	5.0004	4.9755	-0.0249
11	1e+13	NDD	4.975	4.9544	-0.0206
12	1e+13	NDD	4.9819	4.9614	-0.0205
91	0	CORRELATION	4.9651	4.964	-0.0011
92	0	CORRELATION	5.0441	5.0439	-0.0002
93	0	CORRELATION	5.0059	5.0052	-0.0007
94	0	CORRELATION	4.9784	4.978	-0.0004
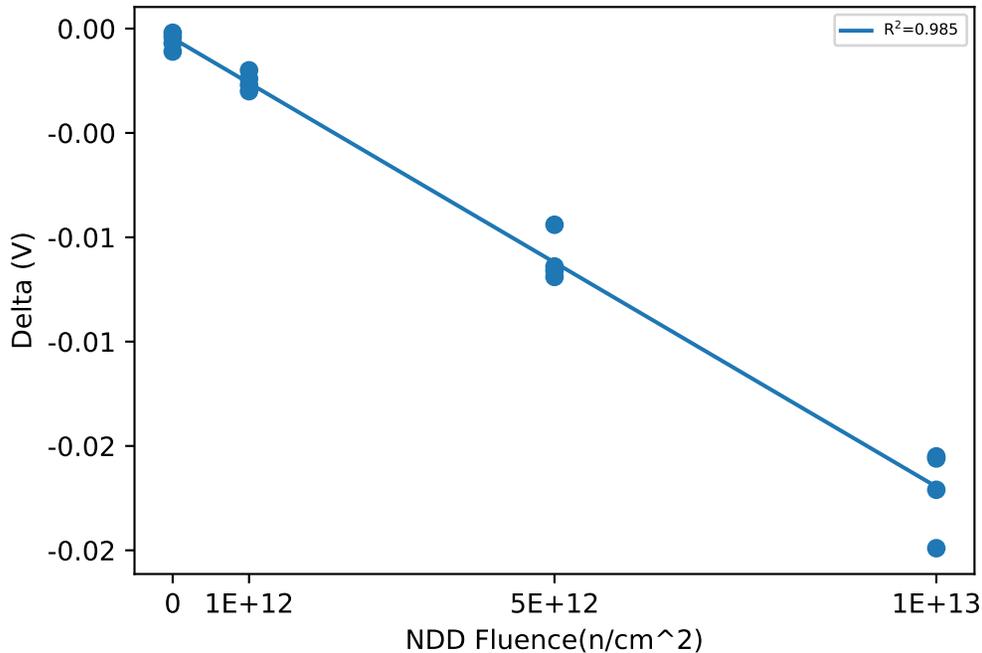
Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9651	4.9984	5.0441	0.034898	4.964	4.9978	5.0439	0.035187	-0.0011	-0.0006	-0.0002	0.00039158
1e+12	4.9985	5.011	5.0234	0.01097	4.9961	5.0085	5.0207	0.010708	-0.003	-0.002525	-0.002	0.0004272
5e+12	4.9763	4.9919	5.014	0.01672	4.9669	4.9808	5.0021	0.015937	-0.0119	-0.011075	-0.0094	0.0011354
1e+13	4.9703	4.9819	5.0004	0.013221	4.9482	4.9599	4.9755	0.01173	-0.0249	-0.022025	-0.0205	0.0020516

Device Test: 15.16 VLDO|V_VLDO/VLDO/12/12/0/0/5/500kHz//@V_LDO_INT

## NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 4.8, Upper Limit = 5.2 (V))

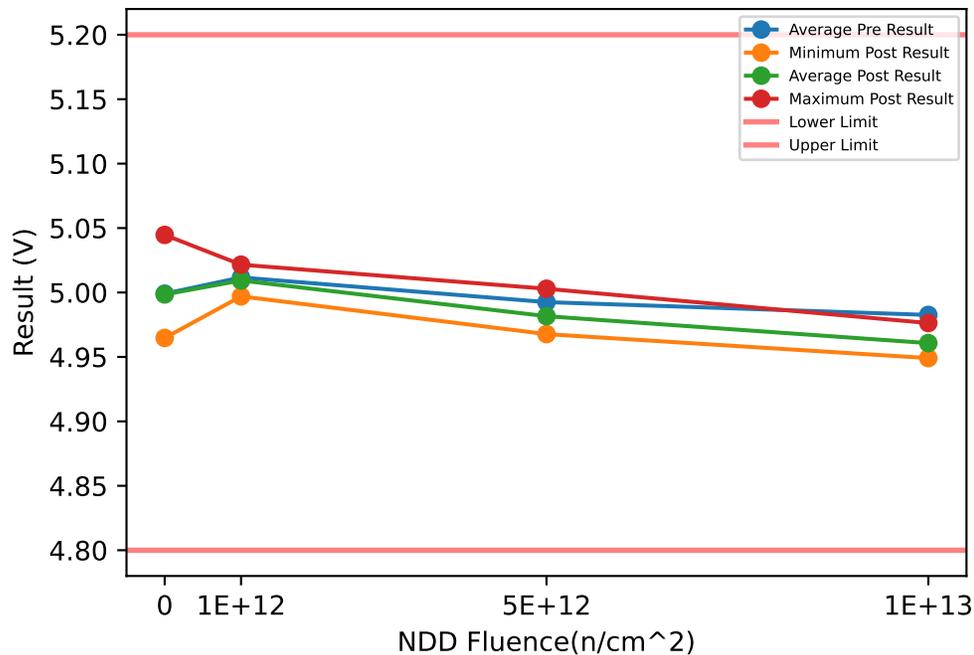| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	4.9991	4.997	-0.0021
2	1e+12	NDD	5.0168	5.0139	-0.0029
3	1e+12	NDD	5.0067	5.0047	-0.002
4	1e+12	NDD	5.0241	5.0216	-0.0025
5	5e+12	NDD	4.9828	4.9712	-0.0116
6	5e+12	NDD	5.0146	5.0029	-0.0117
7	5e+12	NDD	4.9771	4.9677	-0.0094
8	5e+12	NDD	4.9956	4.9846	-0.011
9	1e+13	NDD	4.971	4.9491	-0.0219
10	1e+13	NDD	5.0012	4.9763	-0.0249
11	1e+13	NDD	4.9757	4.9551	-0.0206
12	1e+13	NDD	4.9825	4.9624	-0.0201
91	0	CORRELATION	4.9657	4.9647	-0.001
92	0	CORRELATION	5.0449	5.0447	-0.0002
93	0	CORRELATION	5.0067	5.0059	-0.0008
94	0	CORRELATION	4.979	4.9787	-0.0003
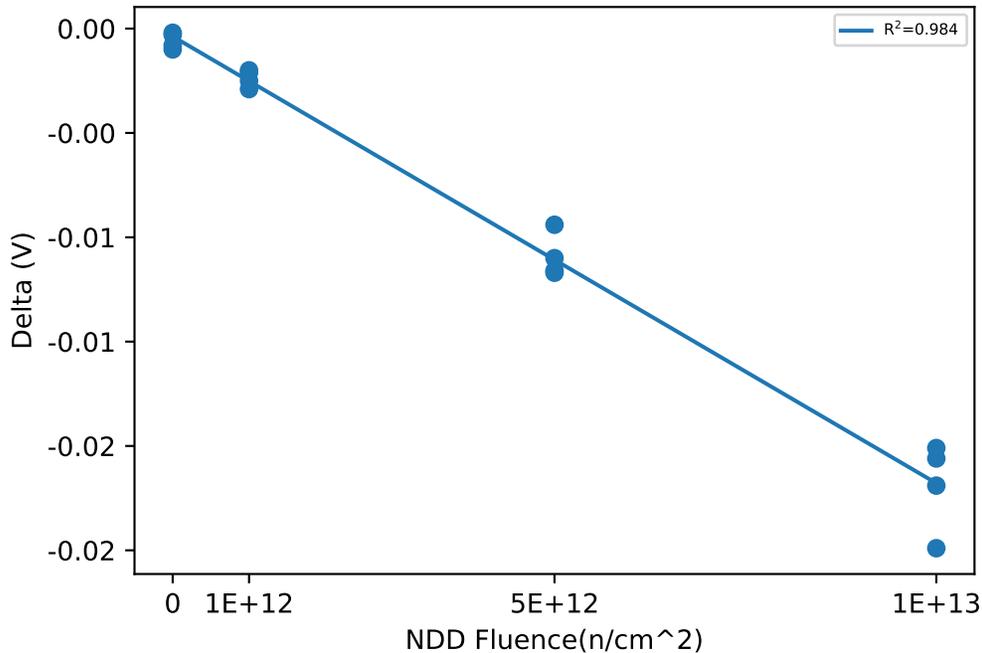
Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9657	4.9991	5.0449	0.035	4.9647	4.9985	5.0447	0.035231	-0.001	-0.000575	-0.0002	0.00038622
1e+12	4.9991	5.0117	5.0241	0.011008	4.997	5.0093	5.0216	0.010722	-0.0029	-0.002375	-0.002	0.0004113
5e+12	4.9771	4.9925	5.0146	0.016626	4.9677	4.9816	5.0029	0.015959	-0.0117	-0.010925	-0.0094	0.0010626
1e+13	4.971	4.9826	5.0012	0.013268	4.9491	4.9607	4.9763	0.011721	-0.0249	-0.021875	-0.0201	0.0021546

Device Test: 15.17 VLDO|V_VLDO/VLDO/14/14/0/0/5/500kHz//@V_LDO_INT

NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 4.8, Upper Limit = 5.2 (V))

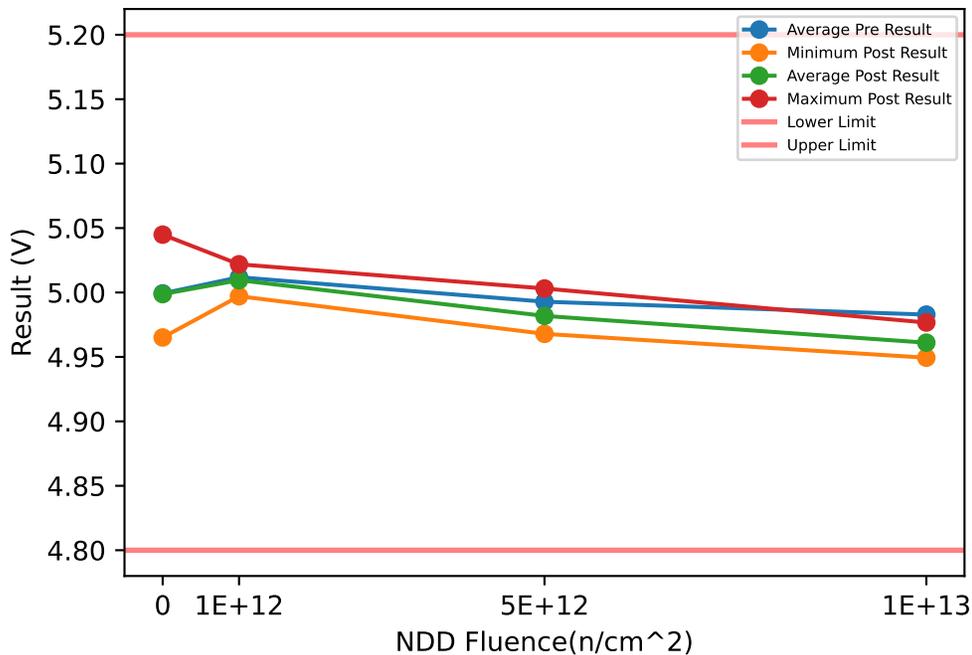| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	4.9992	4.9971	-0.0021
2	1e+12	NDD	5.017	5.0141	-0.0029
3	1e+12	NDD	5.0068	5.0051	-0.0017
4	1e+12	NDD	5.0244	5.0219	-0.0025
5	5e+12	NDD	4.9829	4.9716	-0.0113
6	5e+12	NDD	5.0151	5.0031	-0.012
7	5e+12	NDD	4.9776	4.9679	-0.0097
8	5e+12	NDD	4.9958	4.9847	-0.0111
9	1e+13	NDD	4.9712	4.9494	-0.0218
10	1e+13	NDD	5.0013	4.9767	-0.0246
11	1e+13	NDD	4.9761	4.9555	-0.0206
12	1e+13	NDD	4.9828	4.9626	-0.0202
91	0	CORRELATION	4.9659	4.9651	-0.0008
92	0	CORRELATION	5.0452	5.0449	-0.0003
93	0	CORRELATION	5.0069	5.0061	-0.0008
94	0	CORRELATION	4.9792	4.9789	-0.0003
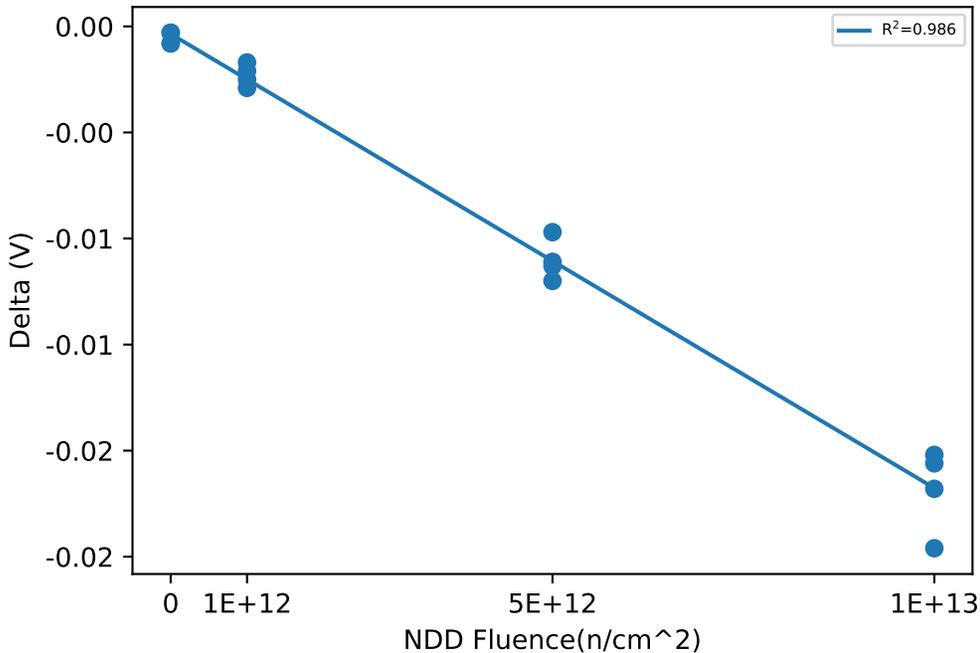
Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9659	4.9993	5.0452	0.035043	4.9651	4.9988	5.0449	0.035167	-0.0008	-0.00055	-0.0003	0.00028868
1e+12	4.9992	5.0118	5.0244	0.011099	4.9971	5.0095	5.0219	0.010771	-0.0029	-0.0023	-0.0017	0.0005164
5e+12	4.9776	4.9928	5.0151	0.016687	4.9679	4.9818	5.0031	0.01591	-0.012	-0.011025	-0.0097	0.00096393
1e+13	4.9712	4.9829	5.0013	0.013187	4.9494	4.9611	4.9767	0.011745	-0.0246	-0.0218	-0.0202	0.0019866

Device Test: 15.19 VLDO|VDO_VLDO/VLDO/8/8/0/0/5/500kHz//@V_LDO_DO_INT

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 0.5 (V))

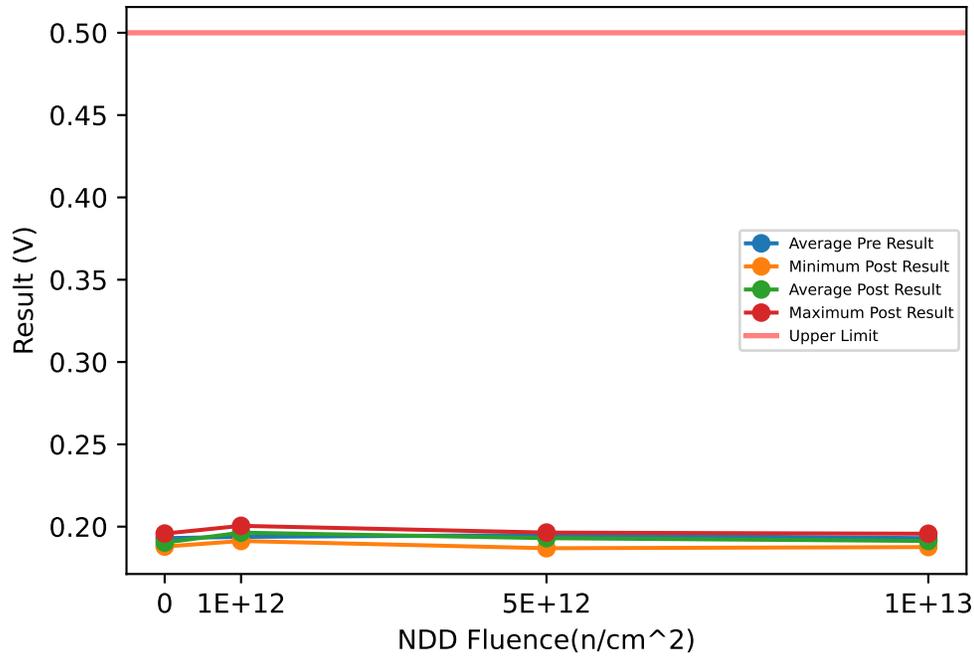| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.1983	0.1913	-0.007
2	1e+12	NDD	0.1906	0.195	0.0044
3	1e+12	NDD	0.1923	0.1987	0.0064
4	1e+12	NDD	0.1939	0.2005	0.0066
5	5e+12	NDD	0.1978	0.1963	-0.0015
6	5e+12	NDD	0.1907	0.1869	-0.0038
7	5e+12	NDD	0.1931	0.1924	-0.0007
8	5e+12	NDD	0.198	0.1964	-0.0016
9	1e+13	NDD	0.1899	0.1924	0.0025
10	1e+13	NDD	0.1911	0.1895	-0.0016
11	1e+13	NDD	0.1932	0.1957	0.0025
12	1e+13	NDD	0.1979	0.1876	-0.0103
91	0	CORRELATION	0.1935	0.1881	-0.0054
92	0	CORRELATION	0.1889	0.1958	0.0069
93	0	CORRELATION	0.1945	0.1879	-0.0066
94	0	CORRELATION	0.1952	0.1894	-0.0058
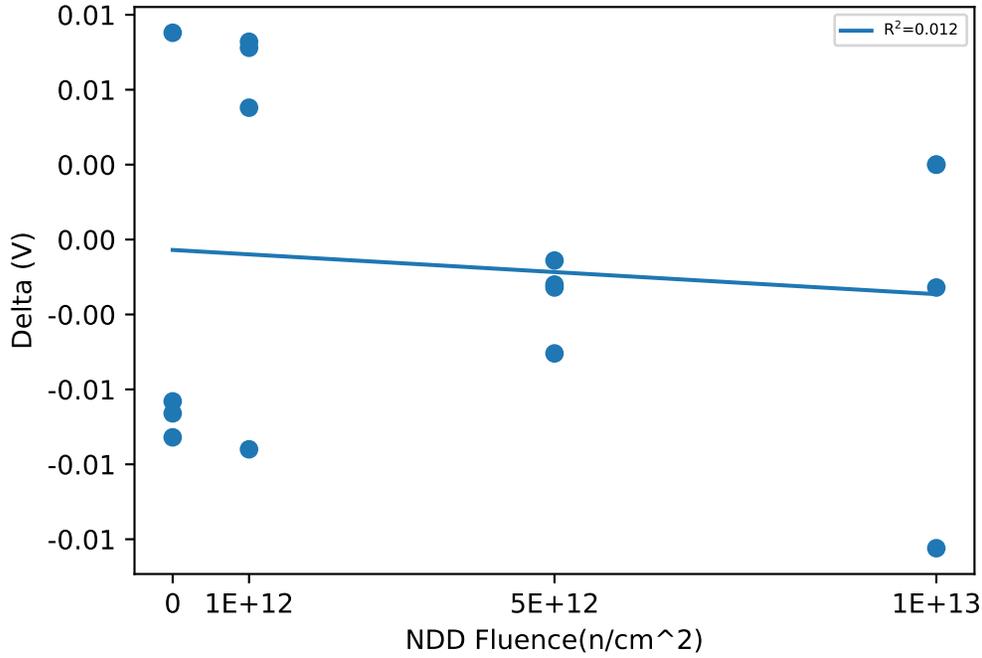
Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1889	0.19303	0.1952	0.0028371	0.1879	0.1903	0.1958	0.0037265	-0.0066	-0.002725	0.0069	0.006436
1e+12	0.1906	0.19378	0.1983	0.0033039	0.1913	0.19637	0.2005	0.0040852	-0.007	0.0026	0.0066	0.0064766
5e+12	0.1907	0.1949	0.198	0.0036009	0.1869	0.193	0.1964	0.0044729	-0.0038	-0.0019	-0.0007	0.0013292
1e+13	0.1899	0.19303	0.1979	0.0035246	0.1876	0.1913	0.1957	0.0035355	-0.0103	-0.001725	0.0025	0.0060346
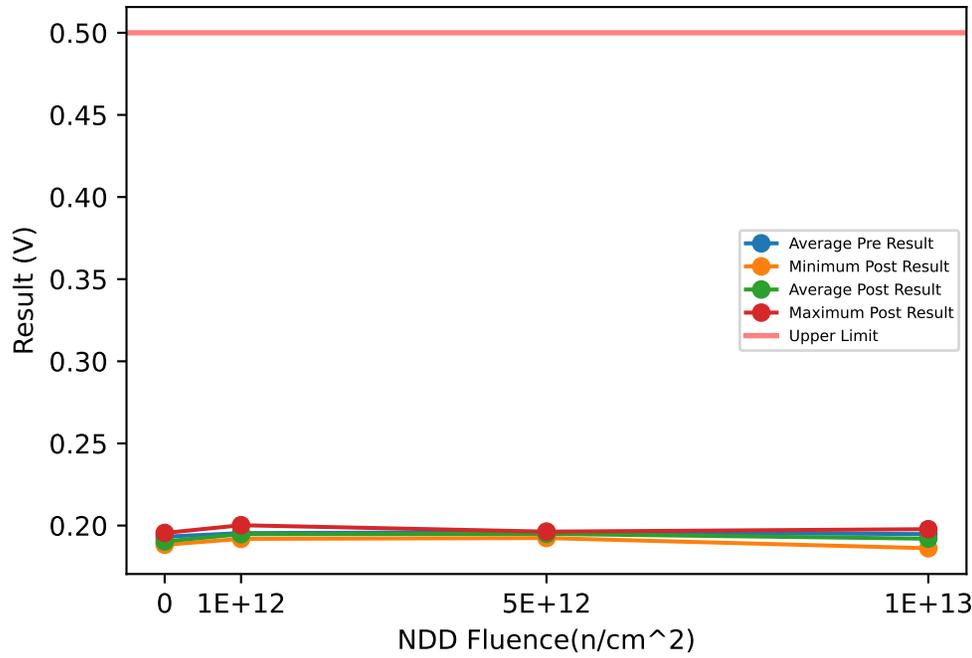
Device Test: 15.20 VLDO|VDO_VLDO/VLDO/12/12/0/0/5/500kHz//@V_LDO_DO_INT

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 0.5 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.1988	0.1919	-0.0069
2	1e+12	NDD	0.1905	0.1948	0.0043
3	1e+12	NDD	0.1981	0.192	-0.0061
4	1e+12	NDD	0.1942	0.2002	0.006
5	5e+12	NDD	0.1979	0.1961	-0.0018
6	5e+12	NDD	0.1949	0.1949	0
7	5e+12	NDD	0.1929	0.1924	-0.0005
8	5e+12	NDD	0.1984	0.1963	-0.0021
9	1e+13	NDD	0.1925	0.1978	0.0053
10	1e+13	NDD	0.1947	0.1968	0.0021
11	1e+13	NDD	0.1941	0.1862	-0.0079
12	1e+13	NDD	0.1979	0.1872	-0.0107
91	0	CORRELATION	0.1937	0.1885	-0.0052
92	0	CORRELATION	0.1891	0.1955	0.0064
93	0	CORRELATION	0.1948	0.1883	-0.0065
94	0	CORRELATION	0.1953	0.1891	-0.0062
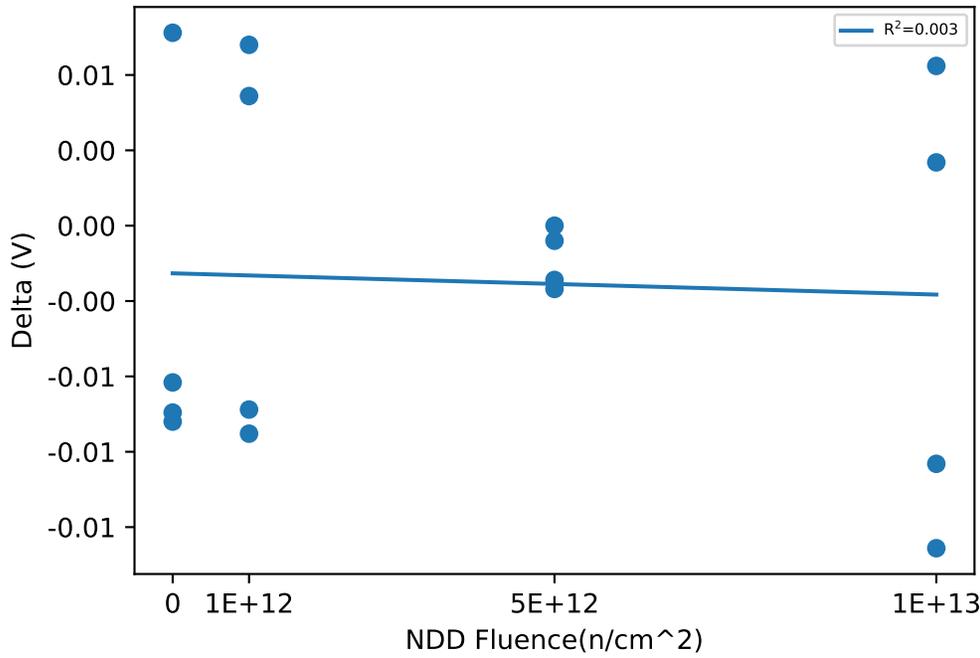
Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1891	0.19323	0.1953	0.00283	0.1883	0.19035	0.1955	0.0034501	-0.0065	-0.002875	0.0064	0.0062083
1e+12	0.1905	0.1954	0.1988	0.0038427	0.1919	0.19472	0.2002	0.0038896	-0.0069	-0.000675	0.006	0.0067697
5e+12	0.1929	0.19603	0.1984	0.0025941	0.1924	0.19492	0.1963	0.0017933	-0.0021	-0.0011	0	0.00101
1e+13	0.1925	0.1948	0.1979	0.0022657	0.1862	0.192	0.1978	0.0061471	-0.0107	-0.0028	0.0053	0.0077037
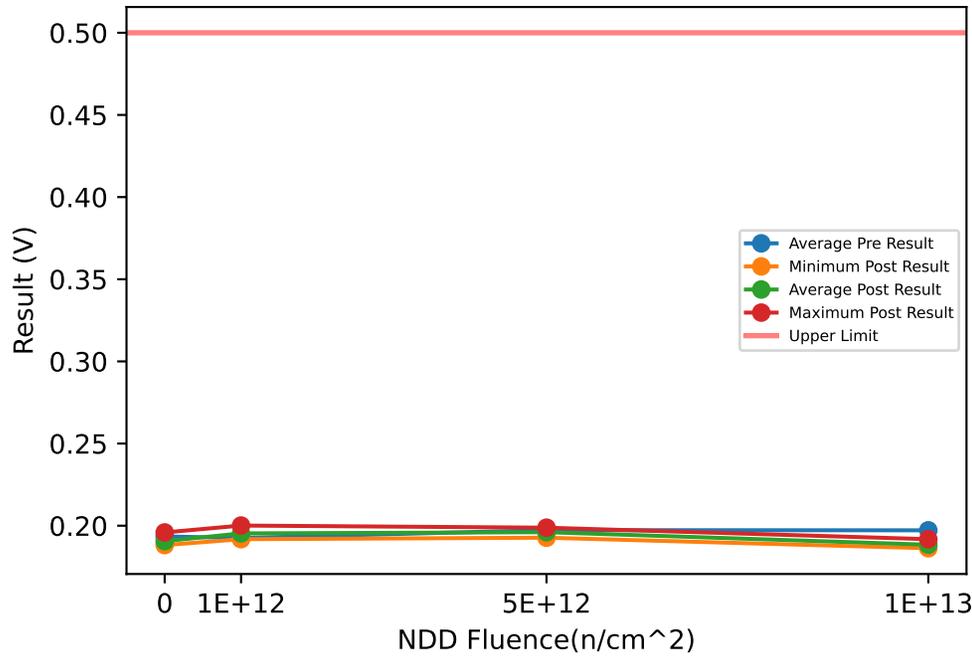
Device Test: 15.21 VLDO|VDO_VLDO/VLDO/14/14/0/0/5/500kHz//@V_LDO_DO_INT

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 0.5 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.1988	0.1918	-0.007
2	1e+12	NDD	0.1898	0.1949	0.0051
3	1e+12	NDD	0.1871	0.1945	0.0074
4	1e+12	NDD	0.1944	0.2001	0.0057
5	5e+12	NDD	0.1984	0.1964	-0.002
6	5e+12	NDD	0.1989	0.1988	-0.0001
7	5e+12	NDD	0.1935	0.1927	-0.0008
8	5e+12	NDD	0.1984	0.1963	-0.0021
9	1e+13	NDD	0.1954	0.1874	-0.008
10	1e+13	NDD	0.1984	0.1863	-0.0121
11	1e+13	NDD	0.1969	0.1918	-0.0051
12	1e+13	NDD	0.1981	0.1882	-0.0099
91	0	CORRELATION	0.1942	0.1882	-0.006
92	0	CORRELATION	0.1891	0.1959	0.0068
93	0	CORRELATION	0.1951	0.1884	-0.0067
94	0	CORRELATION	0.1955	0.1899	-0.0056
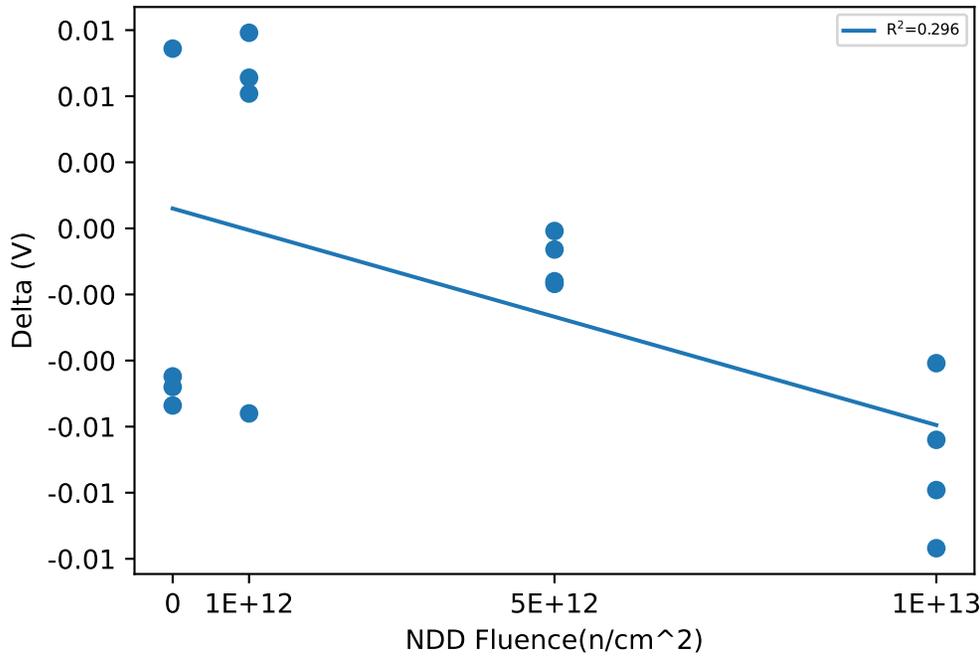
Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1891	0.19348	0.1955	0.0029669	0.1882	0.1906	0.1959	0.0036139	-0.0067	-0.002875	0.0068	0.006466
1e+12	0.1871	0.19253	0.1988	0.0051558	0.1918	0.19532	0.2001	0.0034683	-0.007	0.0028	0.0074	0.0066056
5e+12	0.1935	0.1973	0.1989	0.0025443	0.1927	0.19605	0.1988	0.0025146	-0.0021	-0.00125	-0.0001	0.00096782
1e+13	0.1954	0.1972	0.1984	0.0013638	0.1863	0.18843	0.1918	0.002381	-0.0121	-0.008775	-0.0051	0.002968
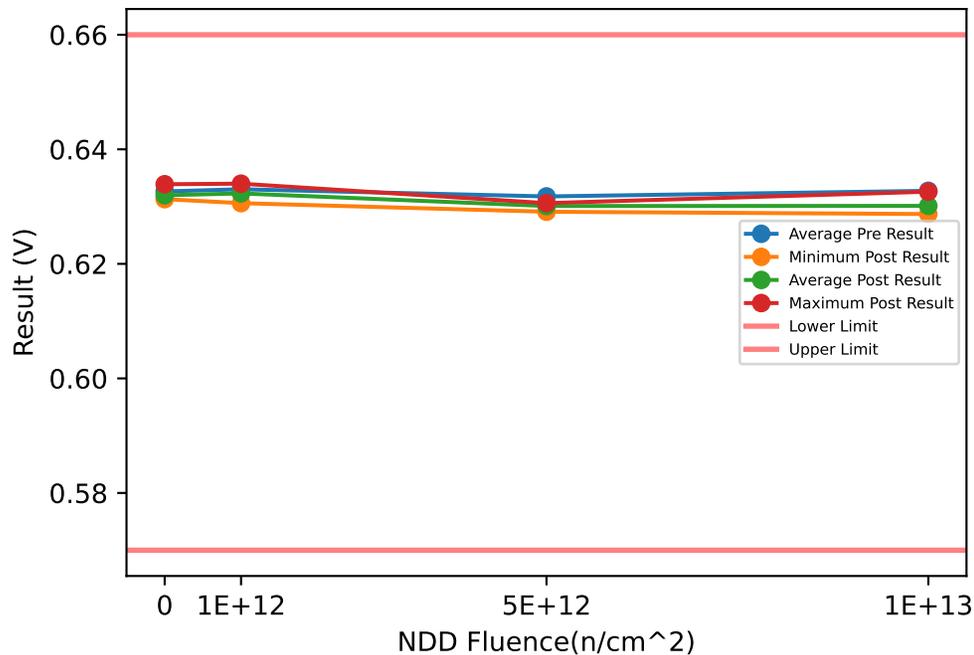
Device Test: 16.10 LEVEL|EN_RISE/EN/14/14/0/0/5/500kHz//@V_EN_RISE

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 0.57, Upper Limit = 0.66 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.6327	0.632	-0.0007
2	1e+12	NDD	0.6332	0.6326	-0.0006
3	1e+12	NDD	0.6313	0.6306	-0.0007
4	1e+12	NDD	0.6349	0.634	-0.0009
5	5e+12	NDD	0.6313	0.6302	-0.0011
6	5e+12	NDD	0.6312	0.6291	-0.0021
7	5e+12	NDD	0.632	0.6306	-0.0014
8	5e+12	NDD	0.6326	0.6305	-0.0021
9	1e+13	NDD	0.6333	0.63	-0.0033
10	1e+13	NDD	0.6318	0.6292	-0.0026
11	1e+13	NDD	0.6353	0.6326	-0.0027
12	1e+13	NDD	0.6306	0.6287	-0.0019
91	0	CORRELATION	0.6319	0.6313	-0.0006
92	0	CORRELATION	0.6318	0.6314	-0.0004
93	0	CORRELATION	0.632	0.6313	-0.0007
94	0	CORRELATION	0.6349	0.6339	-0.001
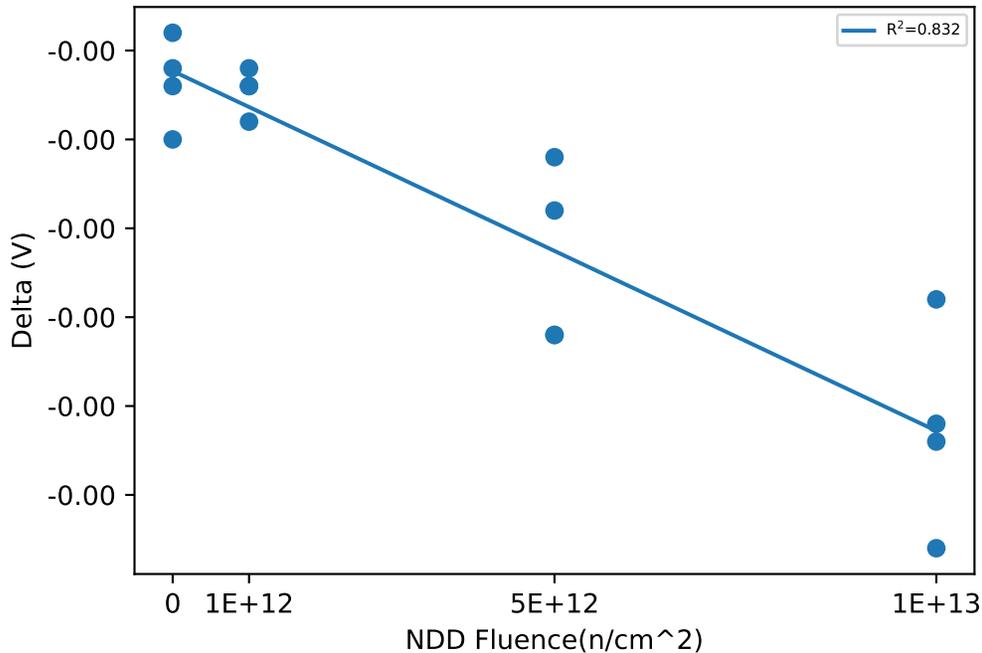
Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.6318	0.63265	0.6349	0.0015022	0.6313	0.63197	0.6339	0.0012842	-0.001	-0.000675	-0.0004	0.00025
1e+12	0.6313	0.63302	0.6349	0.0014863	0.6306	0.6323	0.634	0.0014095	-0.0009	-0.000725	-0.0006	0.00012583
5e+12	0.6312	0.63177	0.6326	0.00065511	0.6291	0.6301	0.6306	0.00068799	-0.0021	-0.001675	-0.0011	0.0005058
1e+13	0.6306	0.63275	0.6353	0.0020273	0.6287	0.63013	0.6326	0.0017347	-0.0033	-0.002625	-0.0019	0.00057373

Device Test: 16.11 LEVEL|EN_FALL/EN/14/14/0/0/5/500kHz//@V_EN_FALL

## NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 0.48, Upper Limit = 0.55 (V))

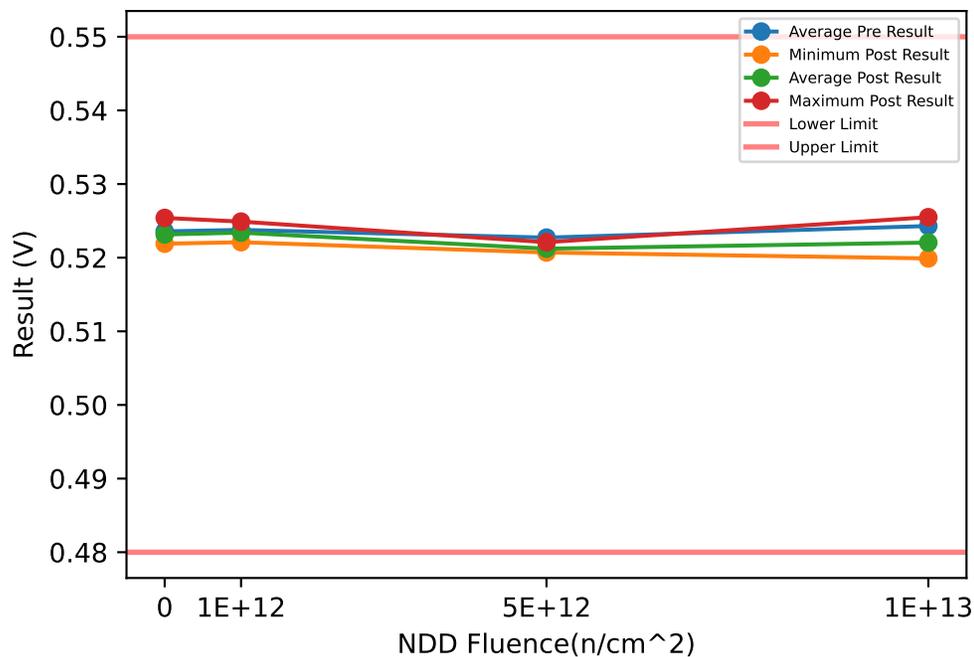| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.5234	0.5232	-0.0002
2	1e+12	NDD	0.5241	0.5234	-0.0007
3	1e+12	NDD	0.5221	0.5221	0
4	1e+12	NDD	0.5255	0.5249	-0.0006
5	5e+12	NDD	0.522	0.5208	-0.0012
6	5e+12	NDD	0.5219	0.5207	-0.0012
7	5e+12	NDD	0.5227	0.5213	-0.0014
8	5e+12	NDD	0.5243	0.5221	-0.0022
9	1e+13	NDD	0.5248	0.5221	-0.0027
10	1e+13	NDD	0.5226	0.5207	-0.0019
11	1e+13	NDD	0.5277	0.5255	-0.0022
12	1e+13	NDD	0.5221	0.5199	-0.0022
91	0	CORRELATION	0.5234	0.5227	-0.0007
92	0	CORRELATION	0.5226	0.5219	-0.0007
93	0	CORRELATION	0.5228	0.5226	-0.0002
94	0	CORRELATION	0.5255	0.5254	-0.0001
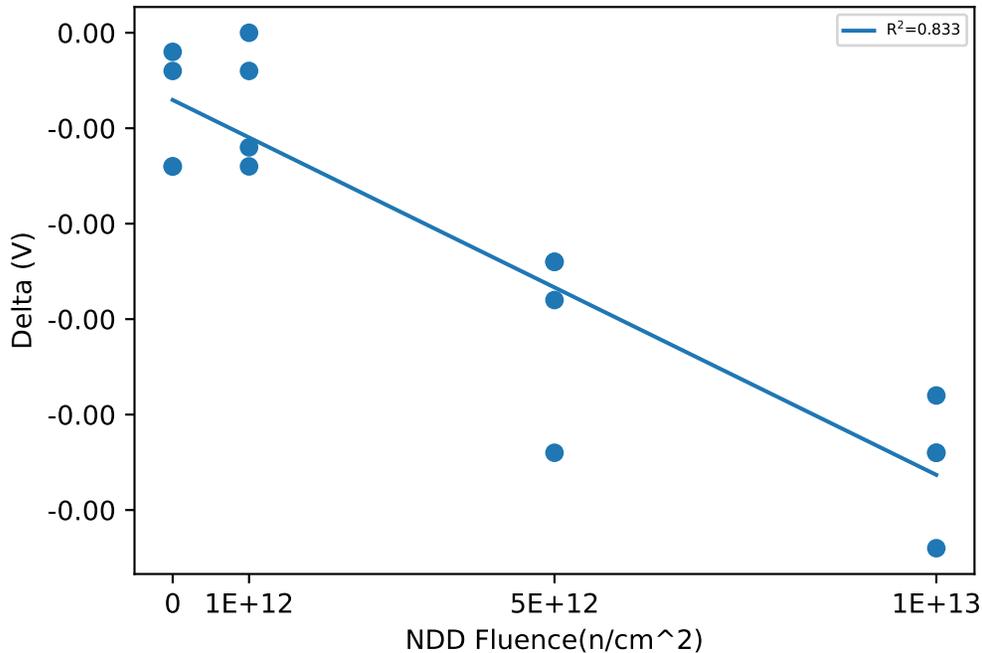
Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5226	0.52358	0.5255	0.0013276	0.5219	0.52315	0.5254	0.0015416	-0.0007	-0.000425	-0.0001	0.00032016
1e+12	0.5221	0.52377	0.5255	0.0014175	0.5221	0.5234	0.5249	0.0011518	-0.0007	-0.000375	0	0.0003304
5e+12	0.5219	0.52272	0.5243	0.0011087	0.5207	0.52123	0.5221	0.00063966	-0.0022	-0.0015	-0.0012	0.0004761
1e+13	0.5221	0.5243	0.5277	0.0025521	0.5199	0.52205	0.5255	0.0024732	-0.0027	-0.00225	-0.0019	0.00033166
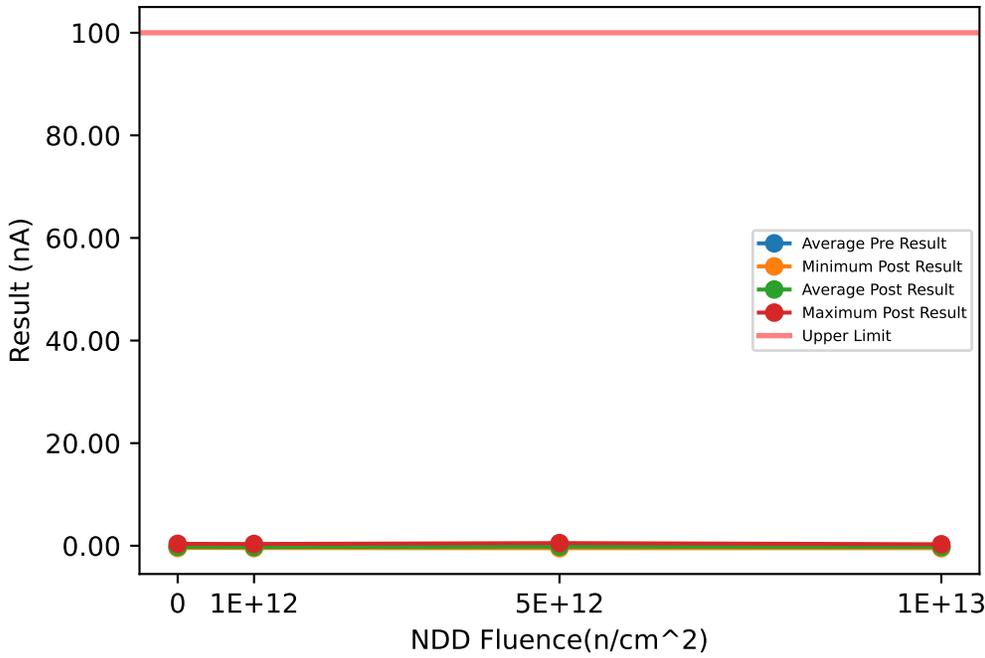
Device Test: 16.13 LEAK|EN_LEAK/EN/14/14/0/0/5/500kHz//@I_EN_LEAK_1V

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 100.0 (nA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	-0.0393	0.3447	0.384
2	1e+12	NDD	-0.373	-0.4531	-0.0801
3	1e+12	NDD	-0.1121	-0.4555	-0.3434
4	1e+12	NDD	-0.1419	-0.4477	-0.3058
5	5e+12	NDD	-0.0331	0.5197	0.5528
6	5e+12	NDD	-0.4542	-0.3095	0.1447
7	5e+12	NDD	-0.187	-0.4836	-0.2966
8	5e+12	NDD	-0.2197	-0.3915	-0.1718
9	1e+13	NDD	-0.0737	0.2885	0.3622
10	1e+13	NDD	-0.5666	-0.475	0.0916
11	1e+13	NDD	-0.2245	-0.3401	-0.1156
12	1e+13	NDD	-0.1512	-0.3666	-0.2154
91	0	CORRELATION	-0.1549	0.3697	0.5246
92	0	CORRELATION	-0.5416	-0.4344	0.1072
93	0	CORRELATION	-0.2838	-0.39	-0.1062
94	0	CORRELATION	-0.2228	-0.3541	-0.1313
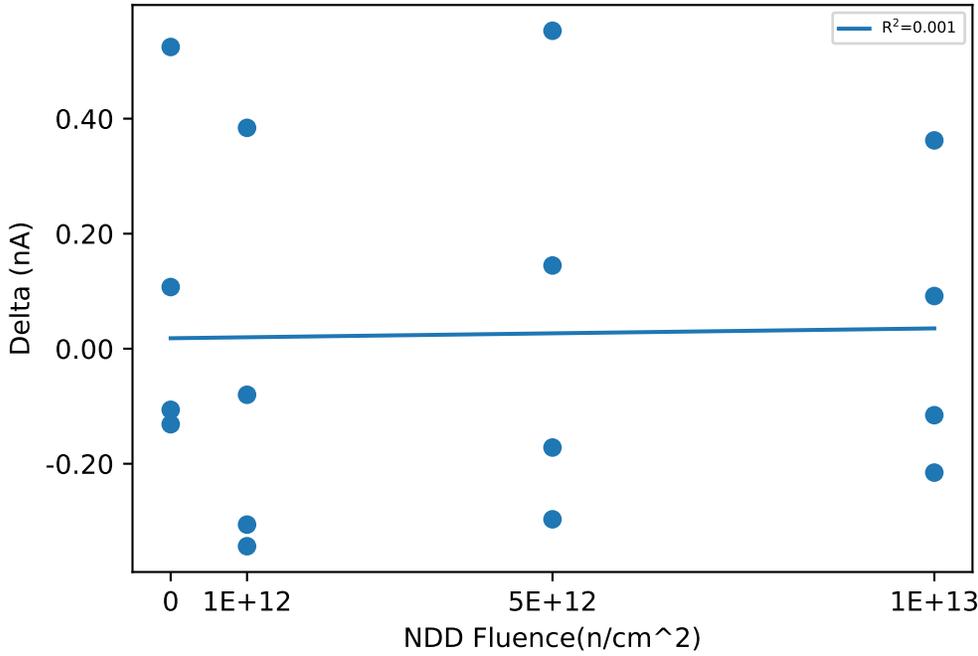
Test Statistics (nA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.5416	-0.30078	-0.1549	0.16896	-0.4344	-0.2022	0.3697	0.38268	-0.1313	0.098575	0.5246	0.30351
1e+12	-0.373	-0.16658	-0.0393	0.14421	-0.4555	-0.2529	0.3447	0.39841	-0.3434	-0.086325	0.384	0.33442
5e+12	-0.4542	-0.2235	-0.0331	0.17399	-0.4836	-0.16622	0.5197	0.46278	-0.2966	0.057275	0.5528	0.37899
1e+13	-0.5666	-0.254	-0.0737	0.21731	-0.475	-0.2233	0.2885	0.34615	-0.2154	0.0307	0.3622	0.25532
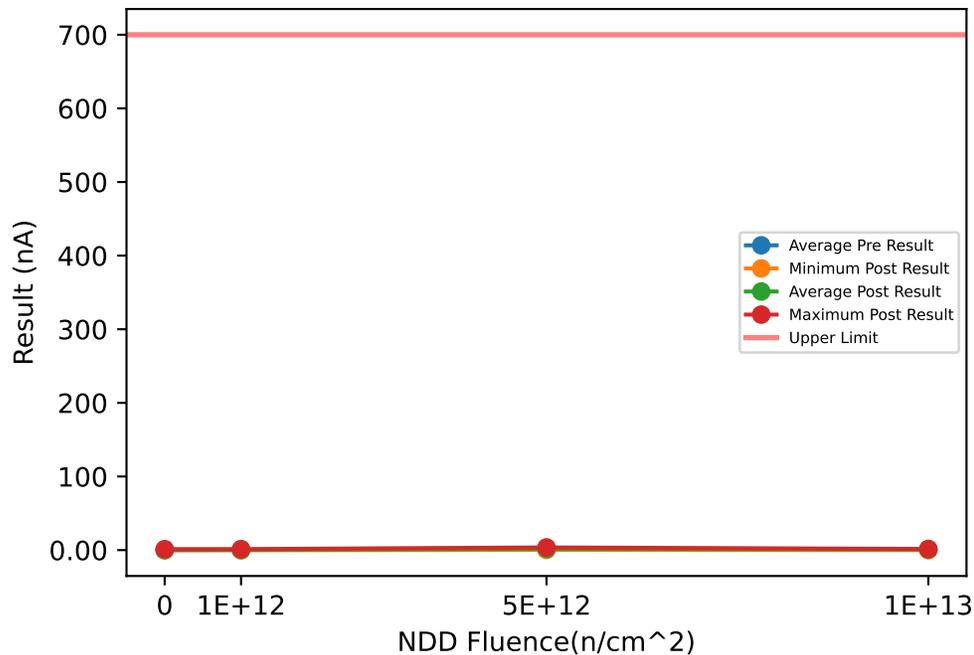
Device Test: 16.14 LEAK|EN_LEAK/EN/14/14/0/0/5/500kHz//@I_EN_LEAK

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 700.0 (nA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.4947	1.3853	0.8906
2	1e+12	NDD	-0.1295	-0.1566	-0.0271
3	1e+12	NDD	0.0159	0.1467	0.1308
4	1e+12	NDD	0.2131	0.0954	-0.1177
5	5e+12	NDD	2.8993	3.6603	0.761
6	5e+12	NDD	0.6885	0.7706	0.0821
7	5e+12	NDD	0.172	0.2871	0.1151
8	5e+12	NDD	2.3431	1.993	-0.3501
9	1e+13	NDD	0.3666	1.5447	1.1781
10	1e+13	NDD	-0.1326	-0.0317	0.1009
11	1e+13	NDD	-0.1028	0.2715	0.3743
12	1e+13	NDD	1.7359	1.5873	-0.1486
91	0	CORRELATION	0.3666	1.3041	0.9375
92	0	CORRELATION	-0.2231	-0.1129	0.1102
93	0	CORRELATION	-0.1714	-0.0155	0.1559
94	0	CORRELATION	0.0419	-0.0826	-0.1245
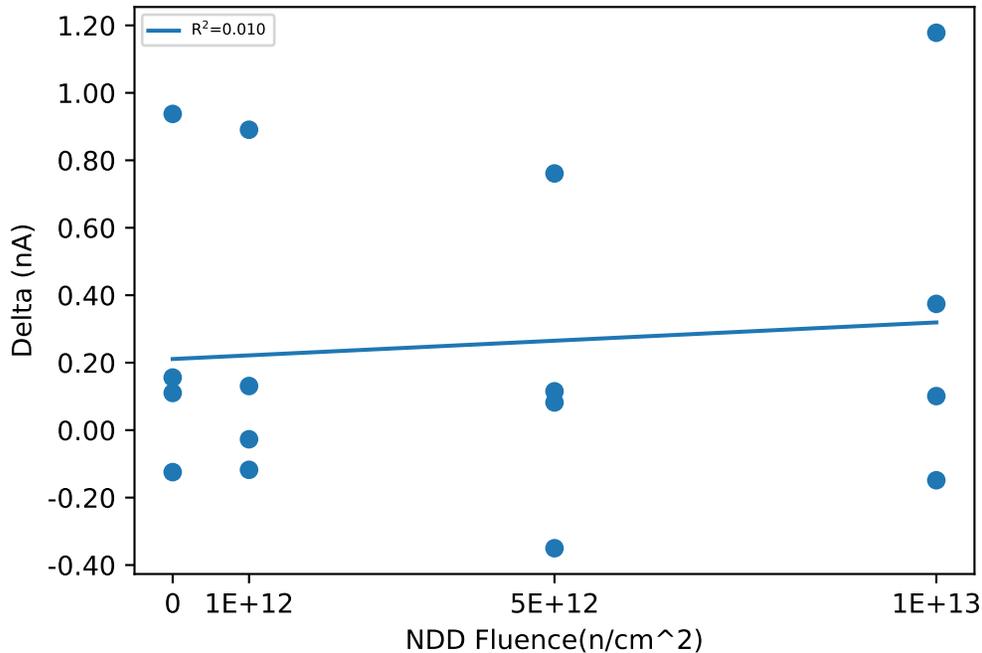
Test Statistics (nA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.2231	0.0035	0.3666	0.26786	-0.1129	0.27327	1.3041	0.68842	-0.1245	0.26977	0.9375	0.46179
1e+12	-0.1295	0.14855	0.4947	0.27012	-0.1566	0.3677	1.3853	0.69123	-0.1177	0.21915	0.8906	0.45926
5e+12	0.172	1.5257	2.8993	1.3023	0.2871	1.6778	3.6603	1.5041	-0.3501	0.15202	0.761	0.45798
1e+13	-0.1326	0.46677	1.7359	0.87643	-0.0317	0.84295	1.5873	0.84421	-0.1486	0.37617	1.1781	0.57569

Device Test: 16.15 LEAK|EN_LEAK/EN/14/14/0/1000/5/500kHz//@I_EN_LEAK_1V

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 100.0 (nA))

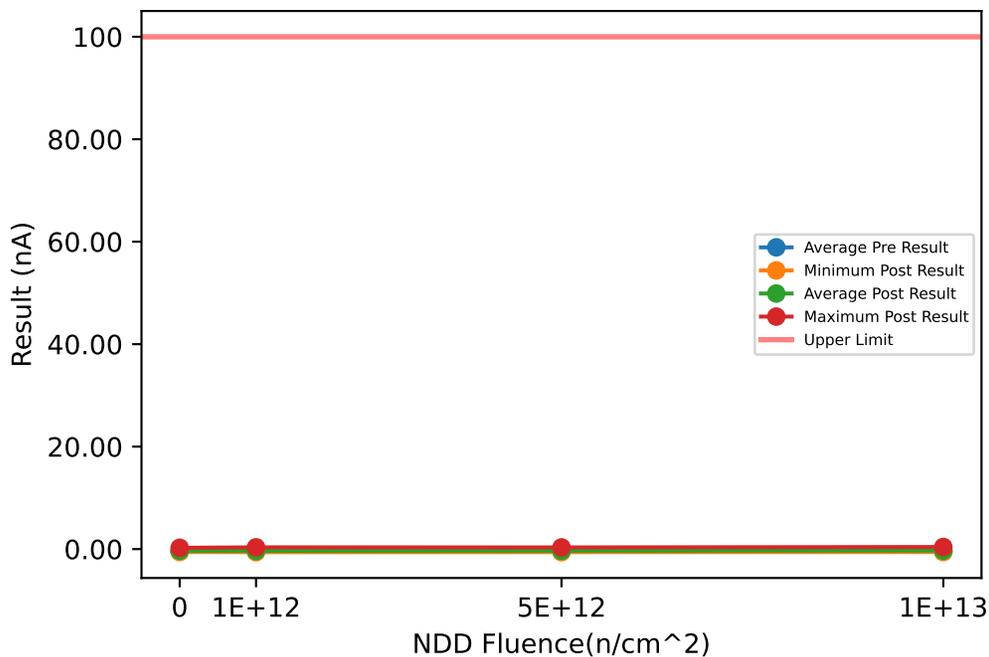| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	-0.411	0.3447	0.7557
2	1e+12	NDD	-0.6103	-0.6123	-0.002
3	1e+12	NDD	-0.4181	-0.5398	-0.1217
4	1e+12	NDD	-0.2259	-0.5382	-0.3123
5	5e+12	NDD	-0.386	0.3291	0.7151
6	5e+12	NDD	-0.6353	-0.5093	0.126
7	5e+12	NDD	-0.4056	-0.6022	-0.1966
8	5e+12	NDD	-0.1605	-0.5101	-0.3496
9	1e+13	NDD	-0.4609	0.4104	0.8713
10	1e+13	NDD	-0.6883	-0.578	0.1103
11	1e+13	NDD	-0.4587	-0.5054	-0.0467
12	1e+13	NDD	-0.2882	-0.4602	-0.172
91	0	CORRELATION	-0.3547	0.2541	0.6088
92	0	CORRELATION	-0.5322	-0.553	-0.0208
93	0	CORRELATION	-0.4056	-0.571	-0.1654
94	0	CORRELATION	-0.2041	-0.4508	-0.2467
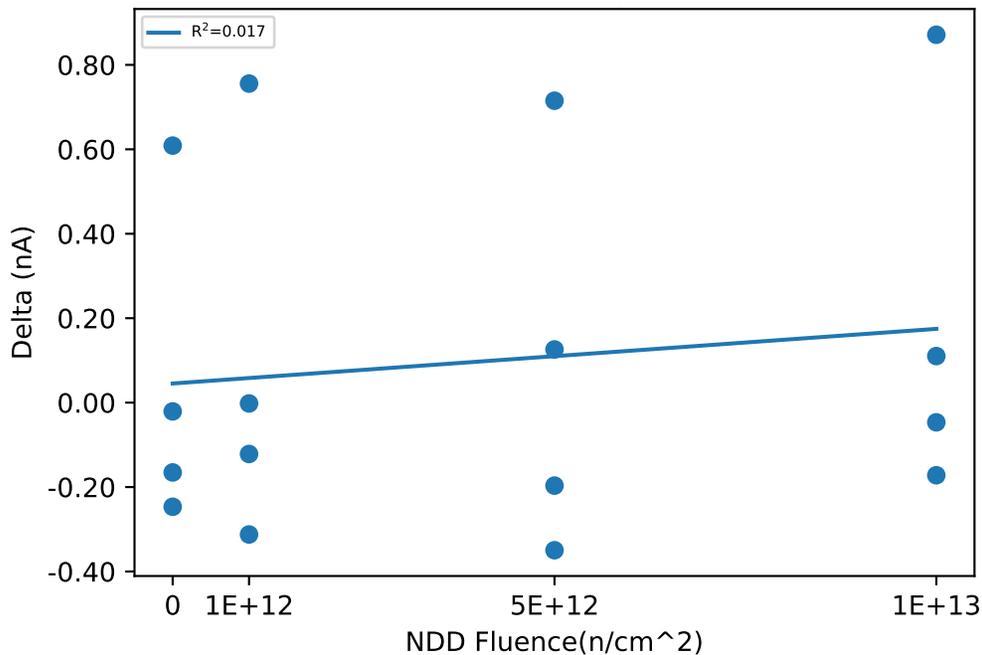
Test Statistics (nA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.5322	-0.37415	-0.2041	0.13573	-0.571	-0.33017	0.2541	0.3931	-0.2467	0.043975	0.6088	0.38797
1e+12	-0.6103	-0.41633	-0.2259	0.15697	-0.6123	-0.3364	0.3447	0.45538	-0.3123	0.079925	0.7557	0.46829
5e+12	-0.6353	-0.39685	-0.1605	0.19401	-0.6022	-0.32312	0.3291	0.437	-0.3496	0.073725	0.7151	0.4713
1e+13	-0.6883	-0.47403	-0.2882	0.16417	-0.578	-0.2833	0.4104	0.46501	-0.172	0.19073	0.8713	0.46818

Device Test: 16.16 LEAK|EN_LEAK/EN/14/14/0/1000/5/500kHz//@I_EN_LEAK

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 700.0 (nA))

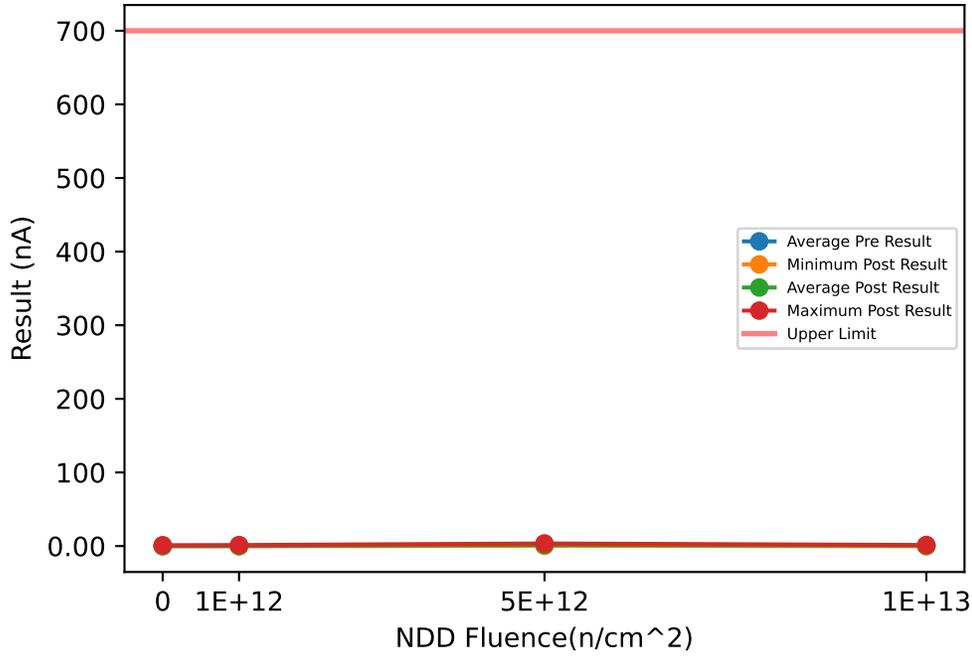| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.2823	1.376	1.0937
2	1e+12	NDD	-0.2918	-0.219	0.0728
3	1e+12	NDD	-0.1496	-0.0218	0.1278
4	1e+12	NDD	0.1477	-0.0108	-0.1585
5	5e+12	NDD	2.765	3.5509	0.7859
6	5e+12	NDD	0.5012	0.5708	0.0696
7	5e+12	NDD	0.0034	0.3339	0.3305
8	5e+12	NDD	2.3556	1.9524	-0.4032
9	1e+13	NDD	0.1605	1.376	1.2155
10	1e+13	NDD	-0.3199	-0.1441	0.1758
11	1e+13	NDD	-0.1995	-0.0343	0.1652
12	1e+13	NDD	1.6425	1.4562	-0.1863
91	0	CORRELATION	0.1074	1.1478	1.0404
92	0	CORRELATION	-0.3917	-0.0941	0.2976
93	0	CORRELATION	-0.1621	0.0781	0.2402
94	0	CORRELATION	-0.0235	-0.1044	-0.0809
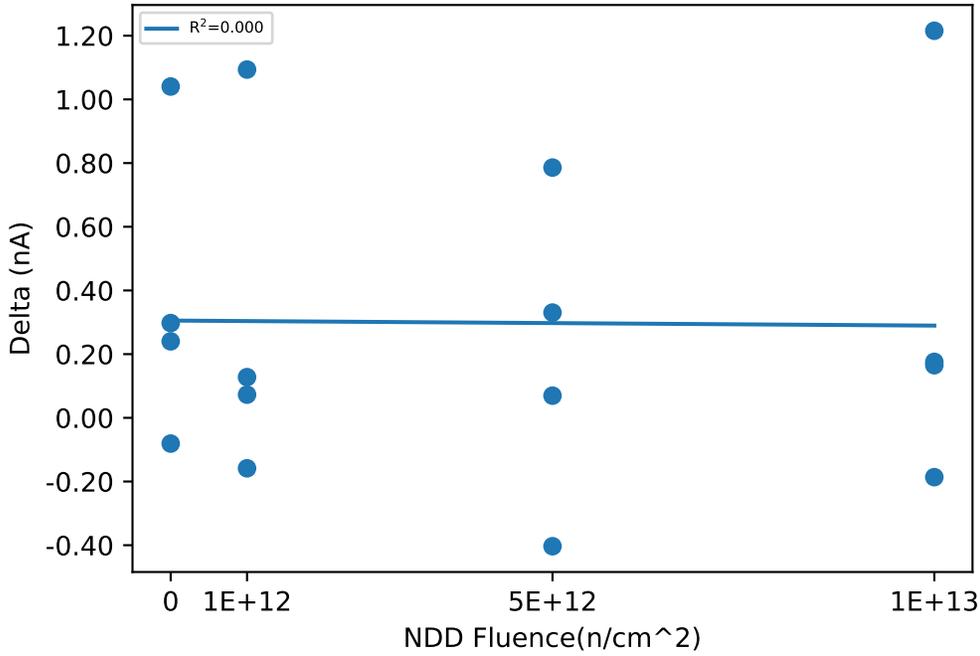
Test Statistics (nA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.3917	-0.11747	0.1074	0.21338	-0.1044	0.25685	1.1478	0.59984	-0.0809	0.37433	1.0404	0.47426
1e+12	-0.2918	-0.00285	0.2823	0.26395	-0.219	0.2811	1.376	0.73617	-0.1585	0.28395	1.0937	0.5539
5e+12	0.0034	1.4063	2.765	1.3583	0.3339	1.602	3.5509	1.4824	-0.4032	0.1957	0.7859	0.49702
1e+13	-0.3199	0.3209	1.6425	0.9044	-0.1441	0.66345	1.4562	0.87086	-0.1863	0.34255	1.2155	0.6058

Device Test: 16.17 LEVEL|EN_RISE/EN/8/8/0/0/5/500kHz//@V_EN_RISE

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 0.57, Upper Limit = 0.66 (V))

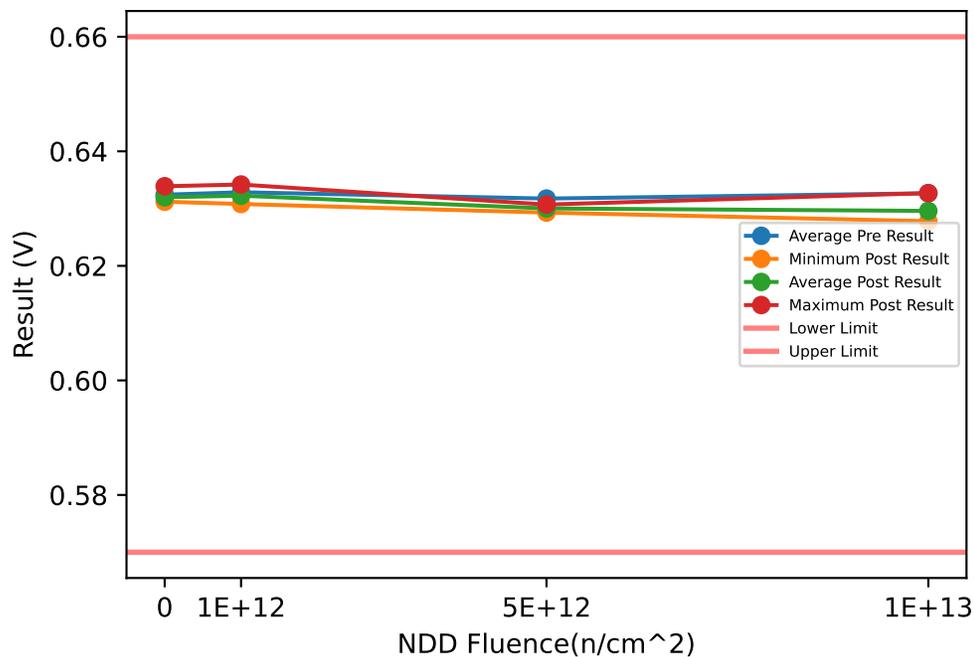| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.6321	0.632	-0.0001
2	1e+12	NDD	0.6332	0.632	-0.0012
3	1e+12	NDD	0.6315	0.6308	-0.0007
4	1e+12	NDD	0.6346	0.6342	-0.0004
5	5e+12	NDD	0.6313	0.6293	-0.002
6	5e+12	NDD	0.6312	0.6294	-0.0018
7	5e+12	NDD	0.6318	0.6307	-0.0011
8	5e+12	NDD	0.6327	0.6307	-0.002
9	1e+13	NDD	0.6327	0.6293	-0.0034
10	1e+13	NDD	0.6318	0.6286	-0.0032
11	1e+13	NDD	0.6355	0.6327	-0.0028
12	1e+13	NDD	0.6307	0.6278	-0.0029
91	0	CORRELATION	0.6319	0.6313	-0.0006
92	0	CORRELATION	0.6318	0.6315	-0.0003
93	0	CORRELATION	0.6313	0.6312	-0.0001
94	0	CORRELATION	0.6347	0.6339	-0.0008
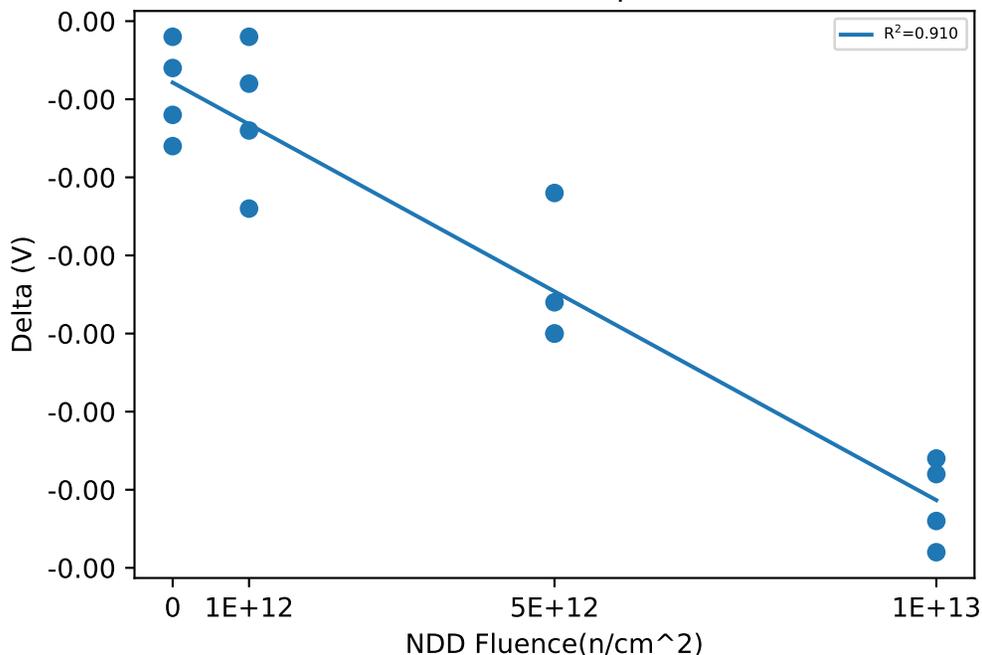
Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.6313	0.63243	0.6347	0.0015392	0.6312	0.63197	0.6339	0.0012894	-0.0008	-0.00045	-0.0001	0.00031091
1e+12	0.6315	0.63285	0.6346	0.0013626	0.6308	0.63225	0.6342	0.0014177	-0.0012	-0.0006	-0.0001	0.00046904
5e+12	0.6312	0.63175	0.6327	0.00068557	0.6293	0.63003	0.6307	0.00078049	-0.002	-0.001725	-0.0011	0.0004272
1e+13	0.6307	0.63267	0.6355	0.0020532	0.6278	0.6296	0.6327	0.0021556	-0.0034	-0.003075	-0.0028	0.00027538

Device Test: 16.18 LEVEL|EN_FALL/EN/8/8/0/0/5/500kHz//@V_EN_FALL

NDD vs Result Stats

Legend:
- Average Pre Result
- Minimum Post Result
- Average Post Result
- Maximum Post Result
- Lower Limit
- Upper Limit

NDD vs Post - Pre Exposure Delta

$R^2=0.750$

Test Results (Lower Limit = 0.48, Upper Limit = 0.55 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.5235	0.5227	-0.0008
2	1e+12	NDD	0.5241	0.5234	-0.0007
3	1e+12	NDD	0.5221	0.5221	0
4	1e+12	NDD	0.5255	0.5249	-0.0006
5	5e+12	NDD	0.5219	0.5207	-0.0012
6	5e+12	NDD	0.522	0.5201	-0.0019
7	5e+12	NDD	0.5227	0.5208	-0.0019
8	5e+12	NDD	0.5234	0.5221	-0.0013
9	1e+13	NDD	0.5249	0.5222	-0.0027
10	1e+13	NDD	0.5226	0.5207	-0.0019
11	1e+13	NDD	0.5267	0.5246	-0.0021
12	1e+13	NDD	0.5214	0.52	-0.0014
91	0	CORRELATION	0.5233	0.5227	-0.0006
92	0	CORRELATION	0.5226	0.5221	-0.0005
93	0	CORRELATION	0.5226	0.522	-0.0006
94	0	CORRELATION	0.5255	0.5249	-0.0006
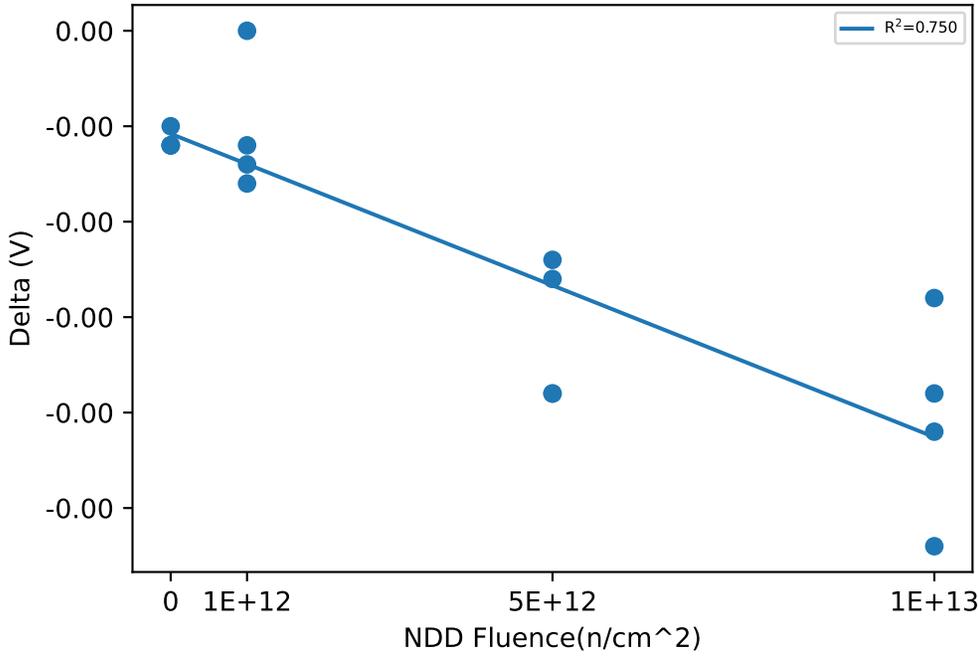
Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5226	0.5235	0.5255	0.0013736	0.522	0.52293	0.5249	0.0013525	-0.0006	-0.000575	-0.0005	5e-05
1e+12	0.5221	0.5238	0.5255	0.0014095	0.5221	0.52328	0.5249	0.0012066	-0.0008	-0.000525	0	0.0003594
5e+12	0.5219	0.5225	0.5234	0.00069761	0.5201	0.52093	0.5221	0.00084212	-0.0019	-0.001575	-0.0012	0.00037749
1e+13	0.5214	0.5239	0.5267	0.002365	0.52	0.52187	0.5246	0.0020353	-0.0027	-0.002025	-0.0014	0.00053774

Device Test: 16.7 LEVEL|EN_RISE/EN/12/12/0/0/5/500kHz//@V_EN_RISE

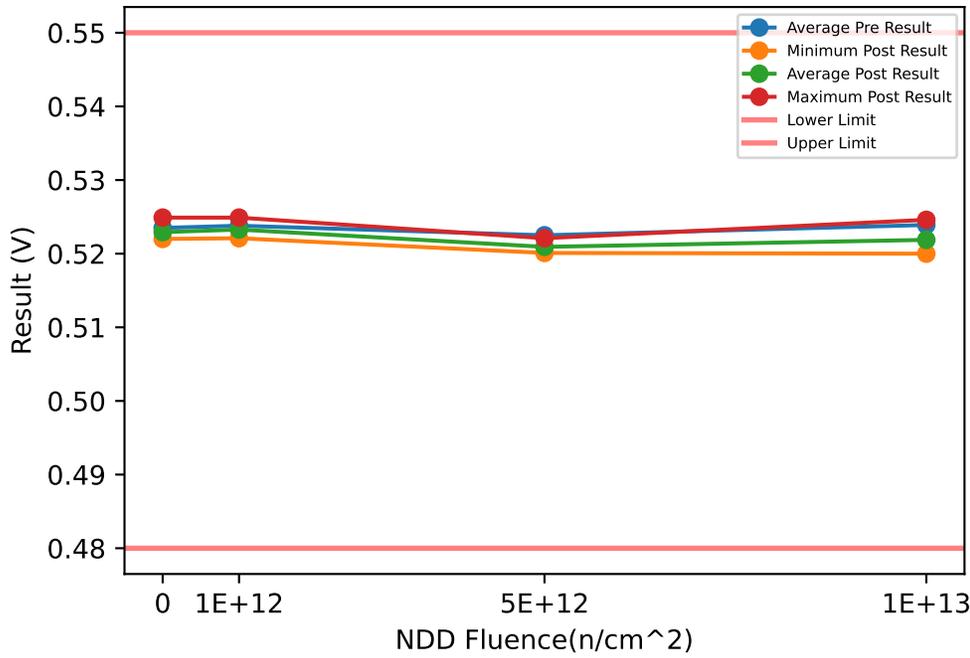## NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 0.57, Upper Limit = 0.66 (V))

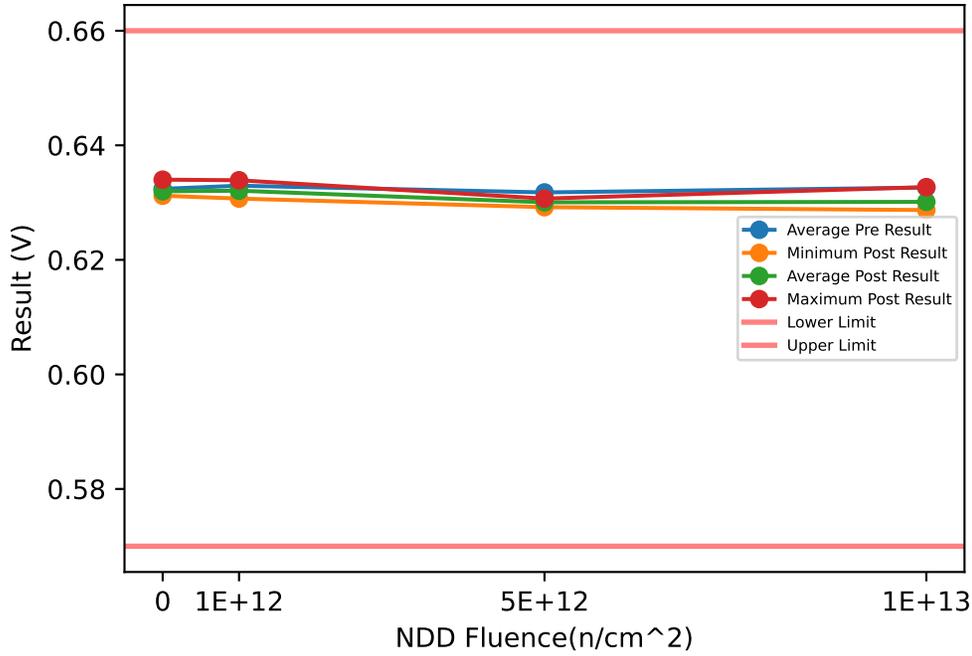| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.6326	0.632	-0.0006
2	1e+12	NDD	0.6332	0.6317	-0.0015
3	1e+12	NDD	0.6313	0.6307	-0.0006
4	1e+12	NDD	0.6347	0.6339	-0.0008
5	5e+12	NDD	0.6314	0.6298	-0.0016
6	5e+12	NDD	0.6313	0.6292	-0.0021
7	5e+12	NDD	0.6318	0.6307	-0.0011
8	5e+12	NDD	0.6326	0.6305	-0.0021
9	1e+13	NDD	0.6327	0.6299	-0.0028
10	1e+13	NDD	0.6318	0.6292	-0.0026
11	1e+13	NDD	0.6353	0.6327	-0.0026
12	1e+13	NDD	0.6307	0.6287	-0.002
91	0	CORRELATION	0.6318	0.6313	-0.0005
92	0	CORRELATION	0.6318	0.6314	-0.0004
93	0	CORRELATION	0.6313	0.6312	-0.0001
94	0	CORRELATION	0.6347	0.634	-0.0007
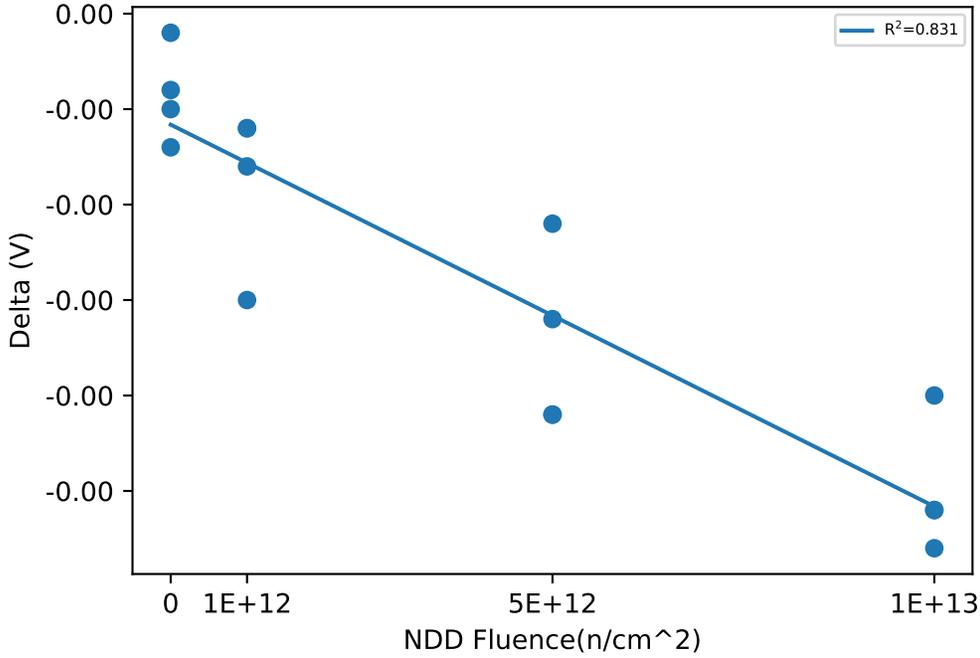
Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.6313	0.6324	0.6347	0.0015513	0.6312	0.63197	0.634	0.0013525	-0.0007	-0.000425	-0.0001	0.00025
1e+12	0.6313	0.63295	0.6347	0.0014107	0.6307	0.63208	0.6339	0.0013376	-0.0015	-0.000875	-0.0006	0.0004272
5e+12	0.6313	0.63177	0.6326	0.0005909	0.6292	0.63005	0.6307	0.00068557	-0.0021	-0.001725	-0.0011	0.00047871
1e+13	0.6307	0.63262	0.6353	0.0019619	0.6287	0.63013	0.6327	0.0017858	-0.0028	-0.0025	-0.002	0.00034641

Device Test: 16.8 LEVEL|EN_FALL/EN/12/12/0/0/5/500kHz//@V_EN_FALL

NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 0.48, Upper Limit = 0.55 (V))

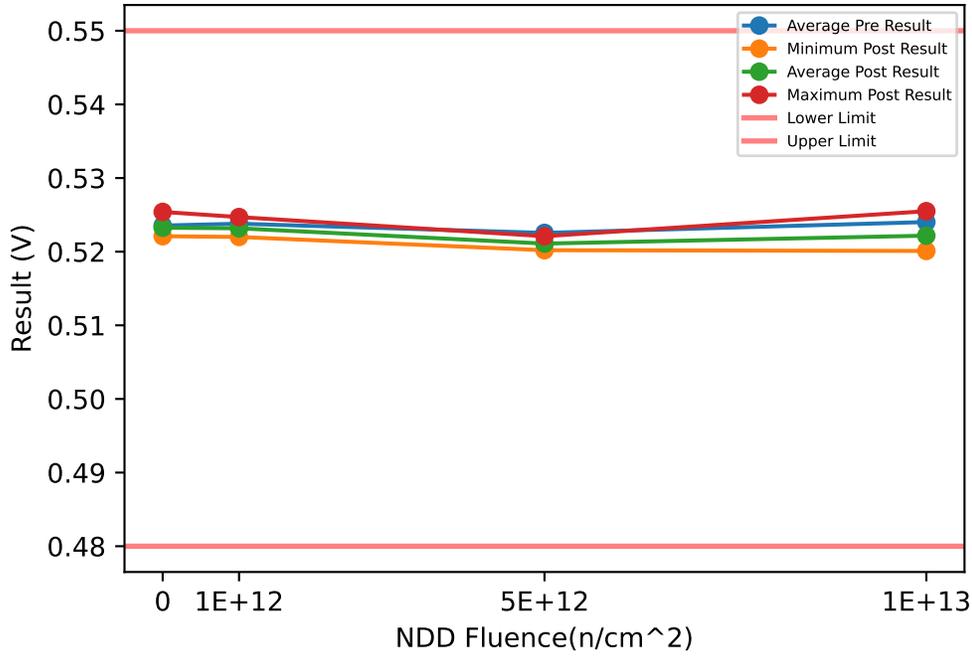| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.5234	0.5227	-0.0007
2	1e+12	NDD	0.5241	0.5233	-0.0008
3	1e+12	NDD	0.5221	0.522	-0.0001
4	1e+12	NDD	0.5256	0.5247	-0.0009
5	5e+12	NDD	0.5221	0.5207	-0.0014
6	5e+12	NDD	0.522	0.5202	-0.0018
7	5e+12	NDD	0.5227	0.5214	-0.0013
8	5e+12	NDD	0.5234	0.5221	-0.0013
9	1e+13	NDD	0.5249	0.5223	-0.0026
10	1e+13	NDD	0.5226	0.5208	-0.0018
11	1e+13	NDD	0.5268	0.5255	-0.0013
12	1e+13	NDD	0.5218	0.5201	-0.0017
91	0	CORRELATION	0.5234	0.5226	-0.0008
92	0	CORRELATION	0.5228	0.5221	-0.0007
93	0	CORRELATION	0.5226	0.5229	0.0003
94	0	CORRELATION	0.5254	0.5254	0
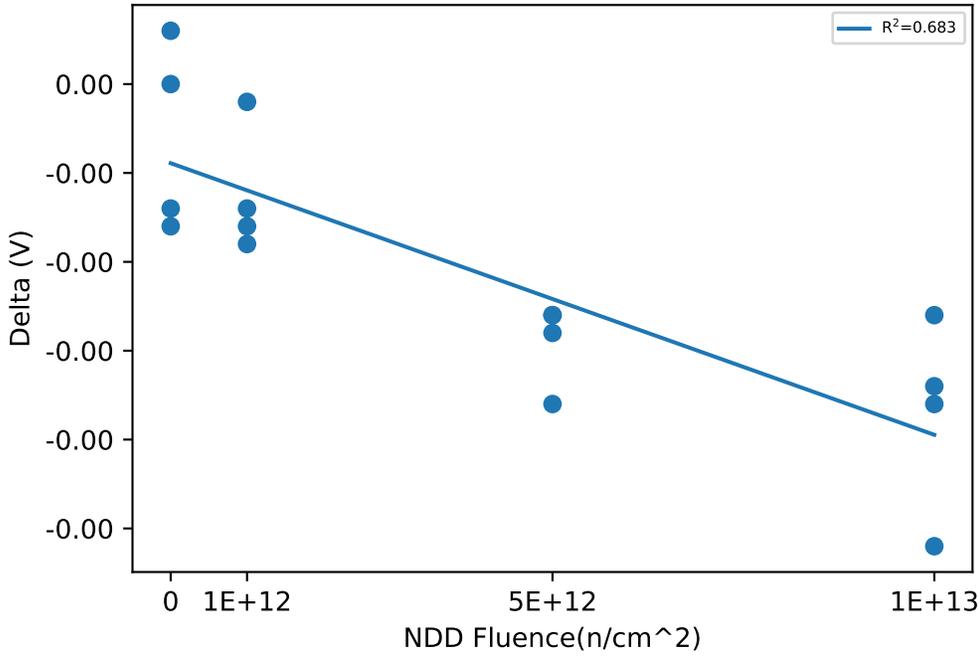
Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5226	0.52355	0.5254	0.0012793	0.5221	0.52325	0.5254	0.0014708	-0.0008	-0.0003	0.0003	0.00053541
1e+12	0.5221	0.5238	0.5256	0.0014583	0.522	0.52318	0.5247	0.0011471	-0.0009	-0.000625	-0.0001	0.0003594
5e+12	0.522	0.52255	0.5234	0.0006455	0.5202	0.5211	0.5221	0.00082865	-0.0018	-0.00145	-0.0013	0.00023805
1e+13	0.5218	0.52402	0.5268	0.0022692	0.5201	0.52218	0.5255	0.0023991	-0.0026	-0.00185	-0.0013	0.00054467
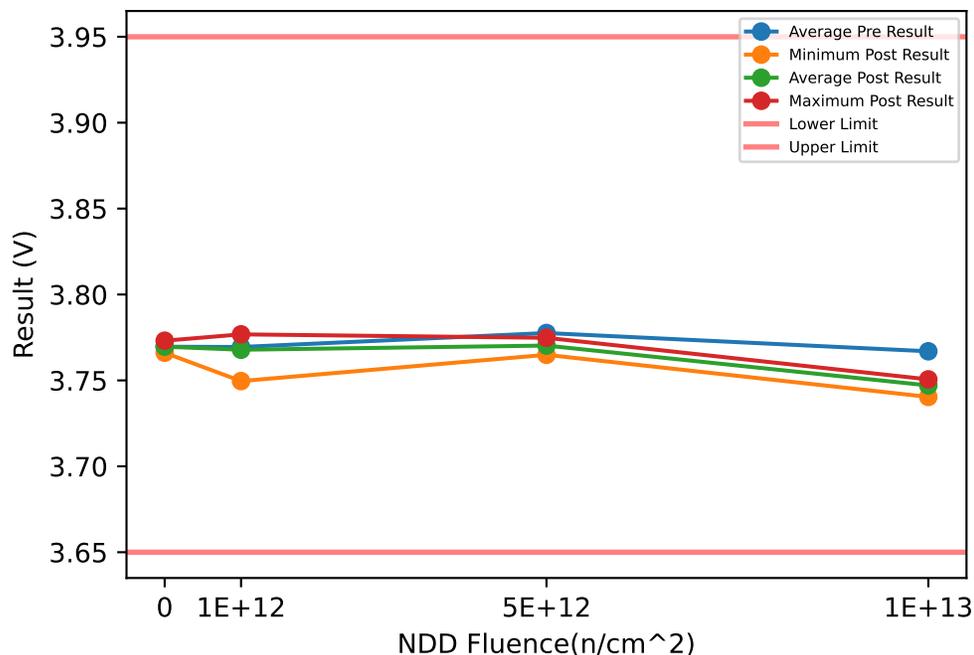
Device Test: 17.10 UVLO|VLDO_RISE/VLDO/4.5/4.5/0/1000/4.5/500kHz//@VLDO_UVLO_RISE

NDD vs Result Stats

## NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 3.65, Upper Limit = 3.95 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	3.7705	3.7685	-0.002
2	1e+12	NDD	3.7786	3.7768	-0.0018
3	1e+12	NDD	3.7768	3.7765	-0.0003
4	1e+12	NDD	3.7519	3.7496	-0.0023
5	5e+12	NDD	3.7817	3.7748	-0.0069
6	5e+12	NDD	3.7786	3.7709	-0.0077
7	5e+12	NDD	3.779	3.7705	-0.0085
8	5e+12	NDD	3.771	3.7649	-0.0061
9	1e+13	NDD	3.7574	3.7404	-0.017
10	1e+13	NDD	3.7689	3.7506	-0.0183
11	1e+13	NDD	3.7799	3.7505	-0.0294
12	1e+13	NDD	3.7616	3.7468	-0.0148
91	0	CORRELATION	3.7686	3.7685	-0.0001
92	0	CORRELATION	3.7733	3.7731	-0.0002
93	0	CORRELATION	3.7715	3.7708	-0.0007
94	0	CORRELATION	3.765	3.7661	0.0011
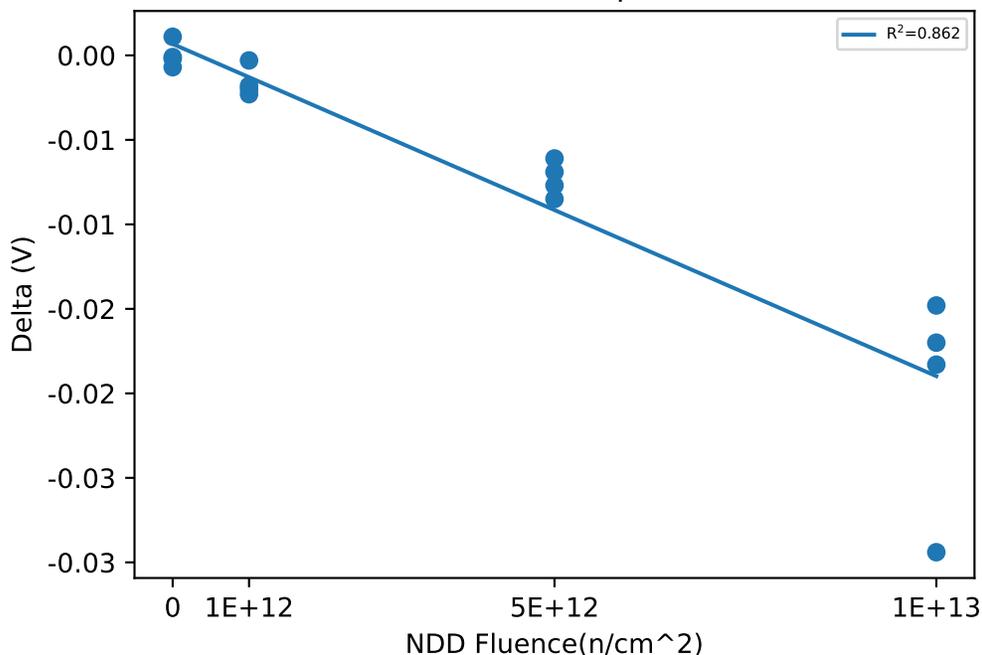
Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.765	3.7696	3.7733	0.0036268	3.7661	3.7696	3.7731	0.0030082	-0.0007	2.5e-05	0.0011	0.00076322
1e+12	3.7519	3.7694	3.7786	0.012205	3.7496	3.7679	3.7768	0.012759	-0.0023	-0.0016	-0.0003	0.00089069
5e+12	3.771	3.7776	3.7817	0.0045945	3.7649	3.7703	3.7748	0.0040746	-0.0085	-0.0073	-0.0061	0.0010328
1e+13	3.7574	3.767	3.7799	0.0098544	3.7404	3.7471	3.7506	0.0047884	-0.0294	-0.019875	-0.0148	0.0065122
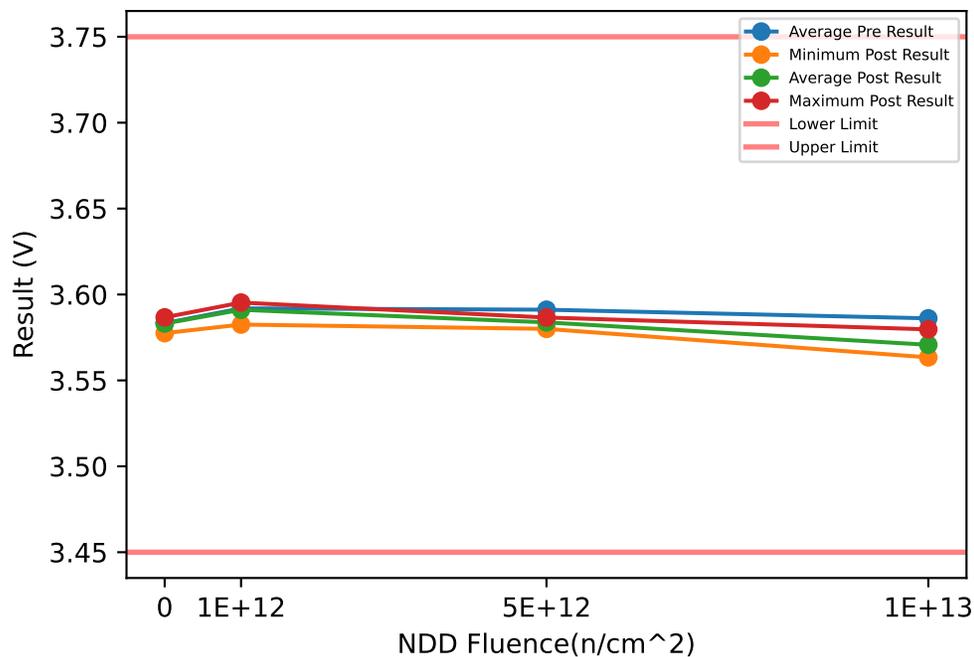
Device Test: 17.11 UVLO|VLDO_FALL/VLDO/4.5/4.5/0/1000/4.5/500kHz//@VLDO_UVLO_FALL

NDD vs Result Stats

## NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 3.45, Upper Limit = 3.75 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	3.5946	3.5934	-0.0012
2	1e+12	NDD	3.5953	3.5932	-0.0021
3	1e+12	NDD	3.5964	3.5953	-0.0011
4	1e+12	NDD	3.5814	3.5825	0.0011
5	5e+12	NDD	3.5946	3.5865	-0.0081
6	5e+12	NDD	3.59	3.582	-0.008
7	5e+12	NDD	3.5876	3.58	-0.0076
8	5e+12	NDD	3.5924	3.5866	-0.0058
9	1e+13	NDD	3.5771	3.5634	-0.0137
10	1e+13	NDD	3.5831	3.5682	-0.0149
11	1e+13	NDD	3.5907	3.5716	-0.0191
12	1e+13	NDD	3.5936	3.5797	-0.0139
91	0	CORRELATION	3.583	3.5837	0.0007
92	0	CORRELATION	3.5878	3.5867	-0.0011
93	0	CORRELATION	3.5854	3.5844	-0.001
94	0	CORRELATION	3.5771	3.5775	0.0004
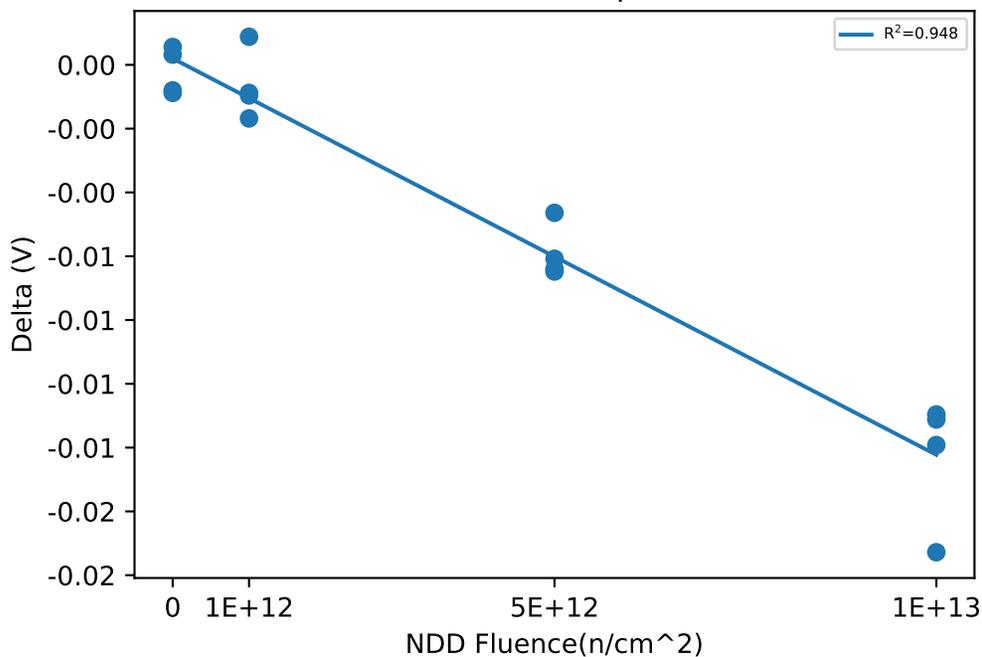
Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.5771	3.5833	3.5878	0.0045894	3.5775	3.5831	3.5867	0.0039314	-0.0011	-0.00025	0.0007	0.00093274
1e+12	3.5814	3.5919	3.5964	0.0070557	3.5825	3.5911	3.5953	0.0058109	-0.0021	-0.000825	0.0011	0.0013598
5e+12	3.5876	3.5911	3.5946	0.0030216	3.58	3.5838	3.5866	0.0033069	-0.0081	-0.007375	-0.0058	0.001072
1e+13	3.5771	3.5861	3.5936	0.0074701	3.5634	3.5707	3.5797	0.0068641	-0.0191	-0.0154	-0.0137	0.0025219
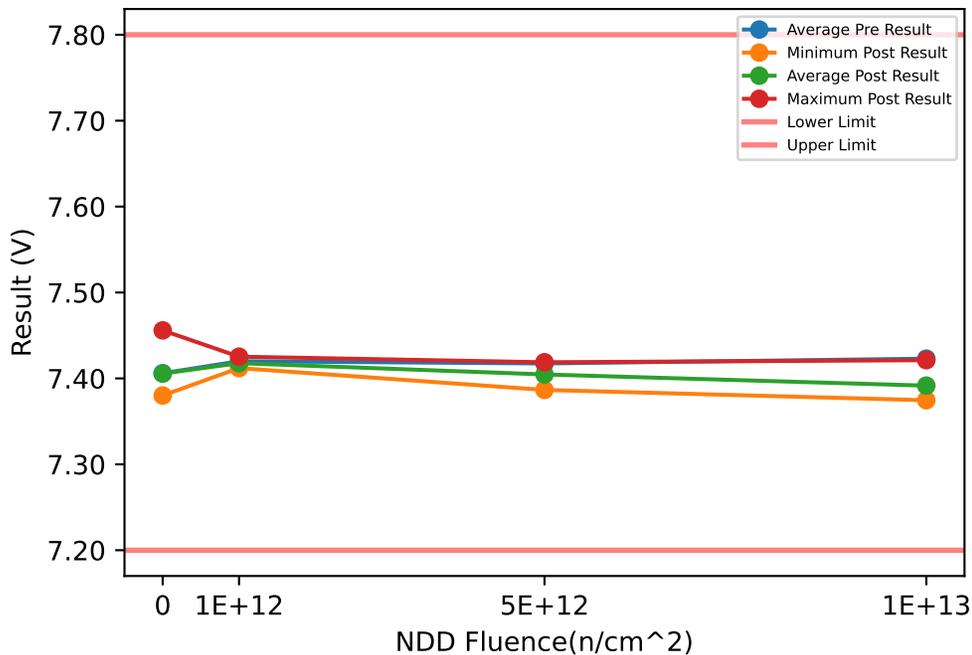
Device Test: 17.13 UVLO|PVIN_RISE/PVIN/4.5/4.5/0/1000/4.5/100kHz//@PVIN_UVLO_RISE_503X

## NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 7.2, Upper Limit = 7.8 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	7.4132	7.412	-0.0012
2	1e+12	NDD	7.428	7.4253	-0.0027
3	1e+12	NDD	7.4228	7.4188	-0.004
4	1e+12	NDD	7.416	7.4148	-0.0012
5	5e+12	NDD	7.4027	7.3866	-0.0161
6	5e+12	NDD	7.4253	7.4132	-0.0121
7	5e+12	NDD	7.4148	7.3999	-0.0149
8	5e+12	NDD	7.4268	7.4188	-0.008
9	1e+13	NDD	7.4092	7.3786	-0.0306
10	1e+13	NDD	7.4228	7.3919	-0.0309
11	1e+13	NDD	7.408	7.3746	-0.0334
12	1e+13	NDD	7.4519	7.4212	-0.0307
91	0	CORRELATION	7.3879	7.3879	0
92	0	CORRELATION	7.4559	7.4559	0
93	0	CORRELATION	7.3987	7.3987	0
94	0	CORRELATION	7.3814	7.3801	-0.0013
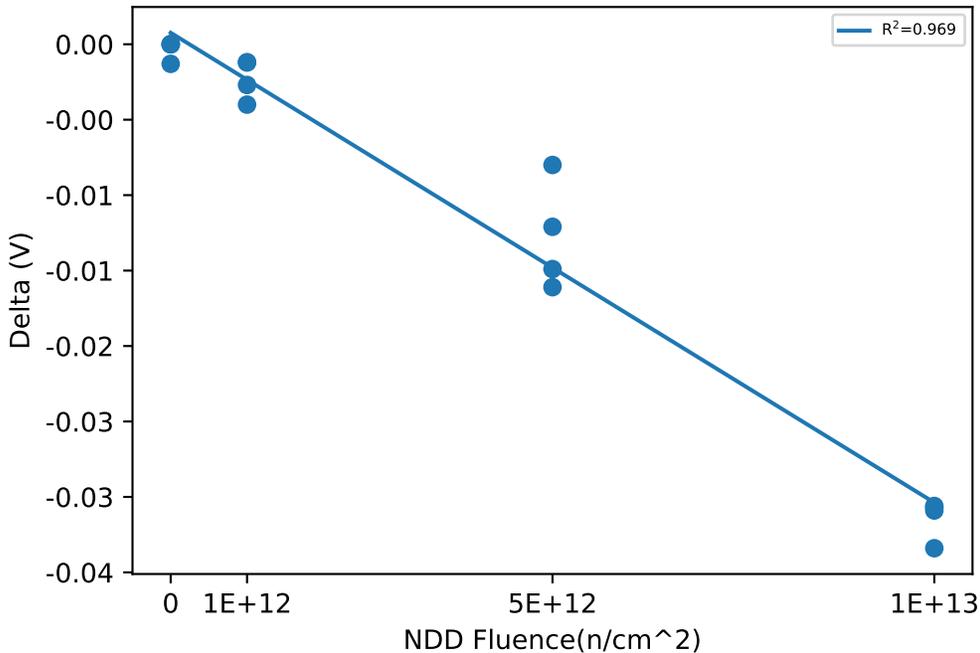
Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.3814	7.406	7.4559	0.03404	7.3801	7.4056	7.4559	0.034357	-0.0013	-0.000325	0	0.00065
1e+12	7.4132	7.42	7.428	0.0066853	7.412	7.4177	7.4253	0.0057697	-0.004	-0.002275	-0.0012	0.00135
5e+12	7.4027	7.4174	7.4268	0.01116	7.3866	7.4046	7.4188	0.014395	-0.0161	-0.012775	-0.008	0.0035976
1e+13	7.408	7.423	7.4519	0.020418	7.3746	7.3916	7.4212	0.021089	-0.0334	-0.0314	-0.0306	0.0013392
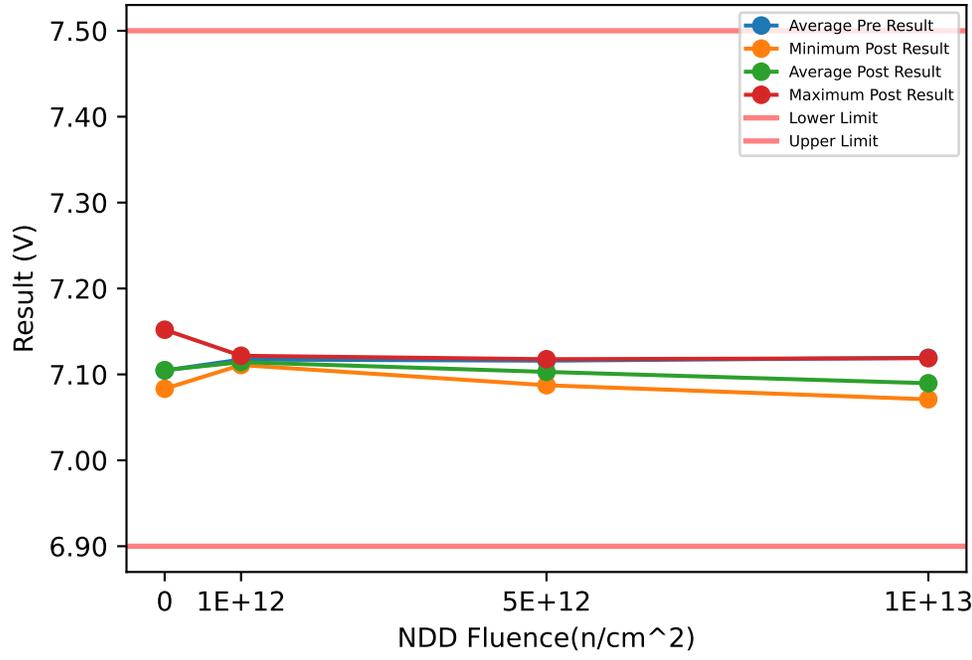
Device Test: 17.14 UVLO|PVIN_FALL/PVIN/4.5/4.5/0/1000/4.5/100kHz//@PVIN_UVLO_FALL_503X

NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 6.9, Upper Limit = 7.5 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	7.1149	7.1109	-0.004
2	1e+12	NDD	7.1245	7.1217	-0.0028
3	1e+12	NDD	7.1149	7.1136	-0.0013
4	1e+12	NDD	7.1149	7.1109	-0.004
5	5e+12	NDD	7.1038	7.0874	-0.0164
6	5e+12	NDD	7.1232	7.1109	-0.0123
7	5e+12	NDD	7.1109	7.0957	-0.0152
8	5e+12	NDD	7.126	7.1177	-0.0083
9	1e+13	NDD	7.1081	7.079	-0.0291
10	1e+13	NDD	7.1189	7.0901	-0.0288
11	1e+13	NDD	7.0997	7.071	-0.0287
12	1e+13	NDD	7.1507	7.1189	-0.0318
91	0	CORRELATION	7.0874	7.0874	0
92	0	CORRELATION	7.1507	7.152	0.0013
93	0	CORRELATION	7.0985	7.097	-0.0015
94	0	CORRELATION	7.0818	7.0833	0.0015
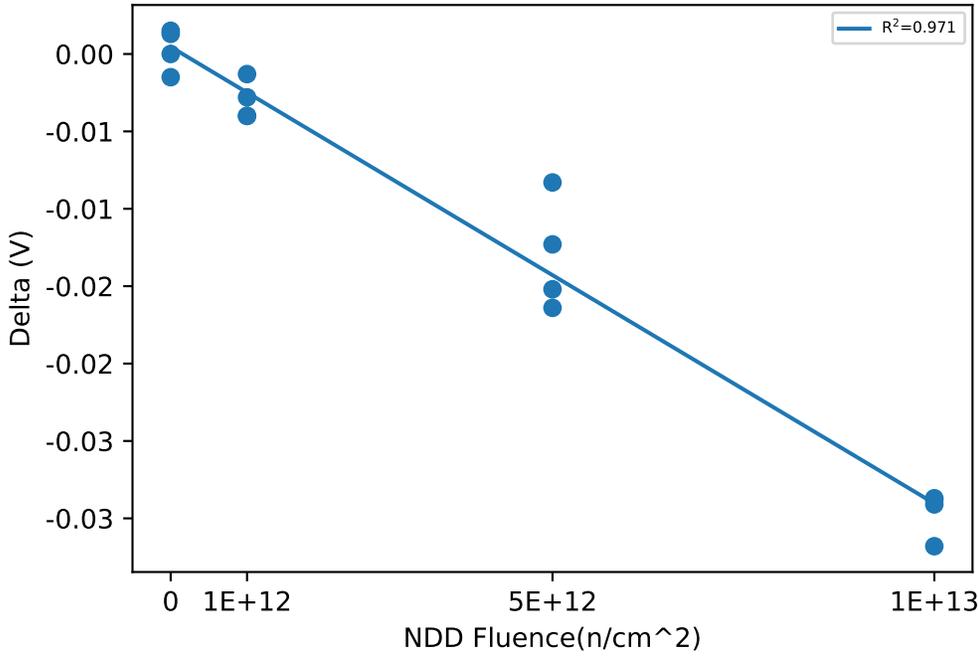
Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0818	7.1046	7.1507	0.031507	7.0833	7.1049	7.152	0.031904	-0.0015	0.000325	0.0015	0.0013865
1e+12	7.1149	7.1173	7.1245	0.0048	7.1109	7.1143	7.1217	0.005111	-0.004	-0.003025	-0.0013	0.0012816
5e+12	7.1038	7.116	7.126	0.010435	7.0874	7.1029	7.1177	0.013846	-0.0164	-0.01305	-0.0083	0.0036042
1e+13	7.0997	7.1193	7.1507	0.022329	7.071	7.0897	7.1189	0.020952	-0.0318	-0.0296	-0.0287	0.0014765
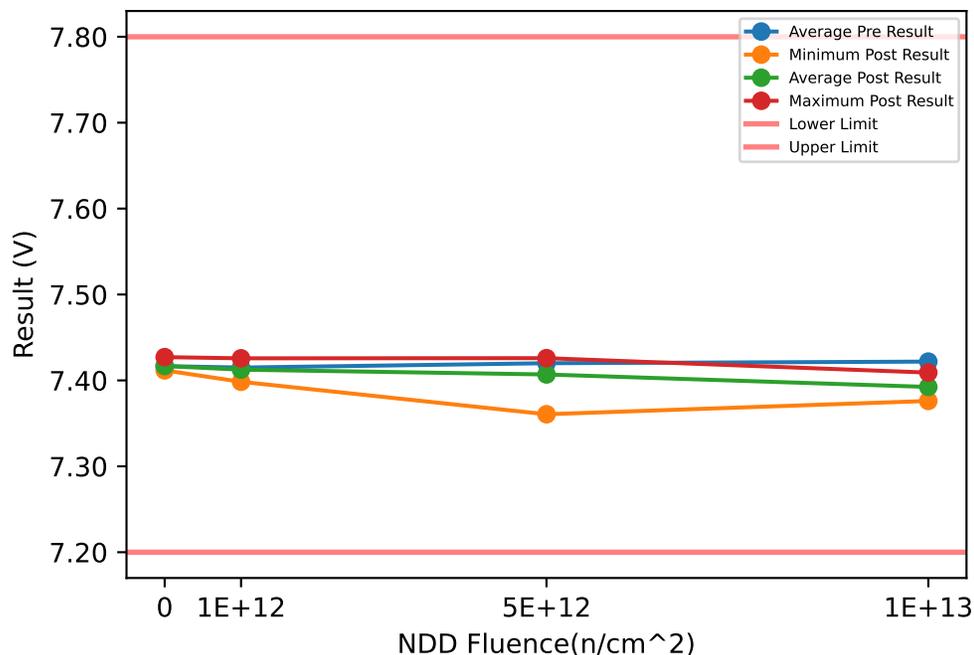
Device Test: 17.16 UVLO|VIN_RISE/VIN/4.5/4.5/0/1000/4.5/100kHz//@VIN_UVLO_RISE_503X

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 7.2, Upper Limit = 7.8 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	7.4077	7.4047	-0.003
2	1e+12	NDD	7.401	7.3984	-0.0026
3	1e+12	NDD	7.4223	7.4212	-0.0011
4	1e+12	NDD	7.4288	7.4257	-0.0031
5	5e+12	NDD	7.3793	7.3606	-0.0187
6	5e+12	NDD	7.4325	7.4199	-0.0126
7	5e+12	NDD	7.4391	7.4259	-0.0132
8	5e+12	NDD	7.4291	7.4213	-0.0078
9	1e+13	NDD	7.4399	7.4091	-0.0308
10	1e+13	NDD	7.4231	7.3943	-0.0288
11	1e+13	NDD	7.4076	7.3761	-0.0315
12	1e+13	NDD	7.4169	7.3901	-0.0268
91	0	CORRELATION	7.4174	7.4163	-0.0011
92	0	CORRELATION	7.4272	7.4271	-0.0001
93	0	CORRELATION	7.412	7.4118	-0.0002
94	0	CORRELATION	7.41	7.4117	0.0017
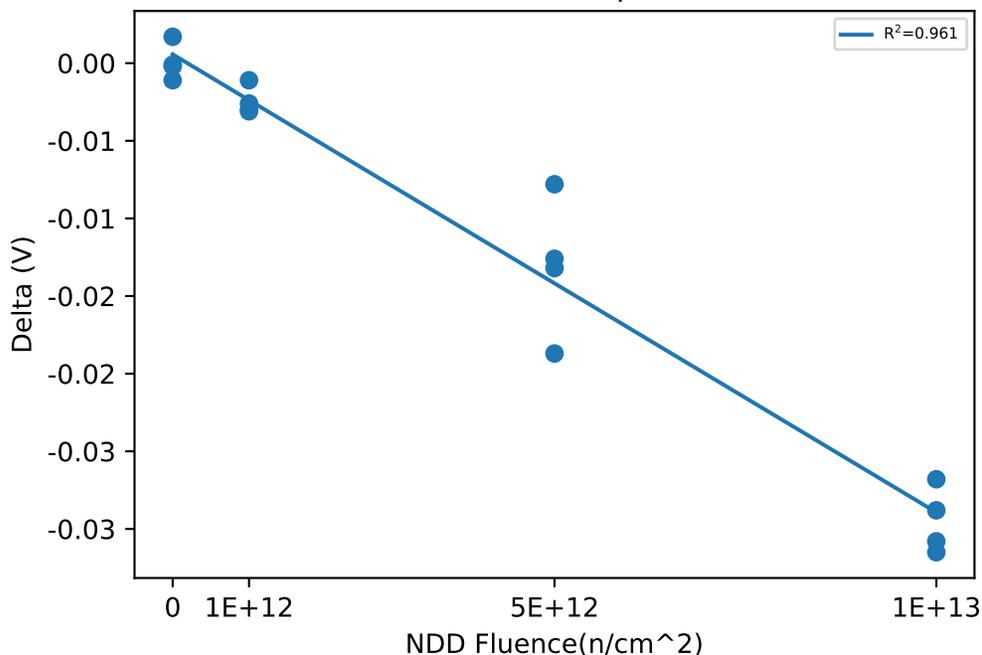
Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.41	7.4166	7.4272	0.0076965	7.4117	7.4167	7.4271	0.0072417	-0.0011	7.5e-05	0.0017	0.001173
1e+12	7.401	7.415	7.4288	0.012819	7.3984	7.4125	7.4257	0.013033	-0.0031	-0.00245	-0.0011	0.00092556
5e+12	7.3793	7.42	7.4391	0.027449	7.3606	7.4069	7.4259	0.03099	-0.0187	-0.013075	-0.0078	0.0044612
1e+13	7.4076	7.4219	7.4399	0.013601	7.3761	7.3924	7.4091	0.013583	-0.0315	-0.029475	-0.0268	0.0021188
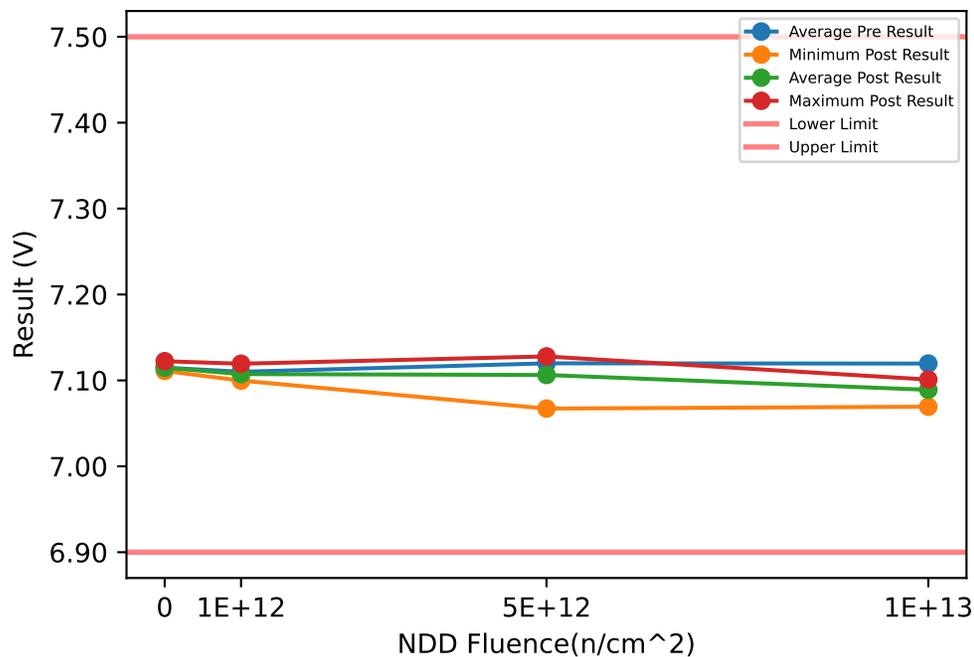
Device Test: 17.17 UVLO|VIN_FALL/VIN/4.5/4.5/0/1000/4.5/100kHz//@VIN_UVLO_FALL_503X

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

R²=0.944

Test Results (Lower Limit = 6.9, Upper Limit = 7.5 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	7.1038	7.0998	-0.004
2	1e+12	NDD	7.104	7.1033	-0.0007
3	1e+12	NDD	7.11	7.1069	-0.0031
4	1e+12	NDD	7.1224	7.1194	-0.003
5	5e+12	NDD	7.0856	7.0672	-0.0184
6	5e+12	NDD	7.1246	7.1158	-0.0088
7	5e+12	NDD	7.1412	7.1279	-0.0133
8	5e+12	NDD	7.1281	7.1144	-0.0137
9	1e+13	NDD	7.135	7.101	-0.034
10	1e+13	NDD	7.1178	7.0908	-0.027
11	1e+13	NDD	7.1047	7.0694	-0.0353
12	1e+13	NDD	7.1209	7.0951	-0.0258
91	0	CORRELATION	7.1119	7.111	-0.0009
92	0	CORRELATION	7.1237	7.1223	-0.0014
93	0	CORRELATION	7.1122	7.1129	0.0007
94	0	CORRELATION	7.1115	7.1129	0.0014
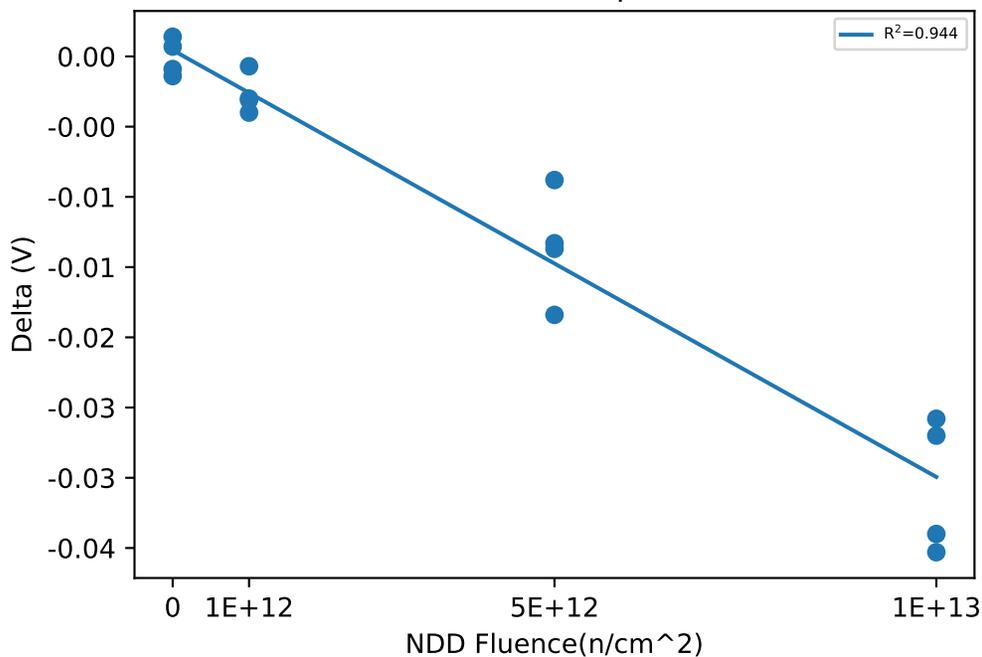
Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.1115	7.1148	7.1237	0.0059236	7.111	7.1148	7.1223	0.005096	-0.0014	-5e-05	0.0014	0.0013178
1e+12	7.1038	7.1101	7.1224	0.0087214	7.0998	7.1074	7.1194	0.0085403	-0.004	-0.0027	-0.0007	0.0014071
5e+12	7.0856	7.1199	7.1412	0.023941	7.0672	7.1063	7.1279	0.026778	-0.0184	-0.01355	-0.0088	0.003923
1e+13	7.1047	7.1196	7.135	0.012438	7.0694	7.0891	7.101	0.013767	-0.0353	-0.030525	-0.0258	0.0048176
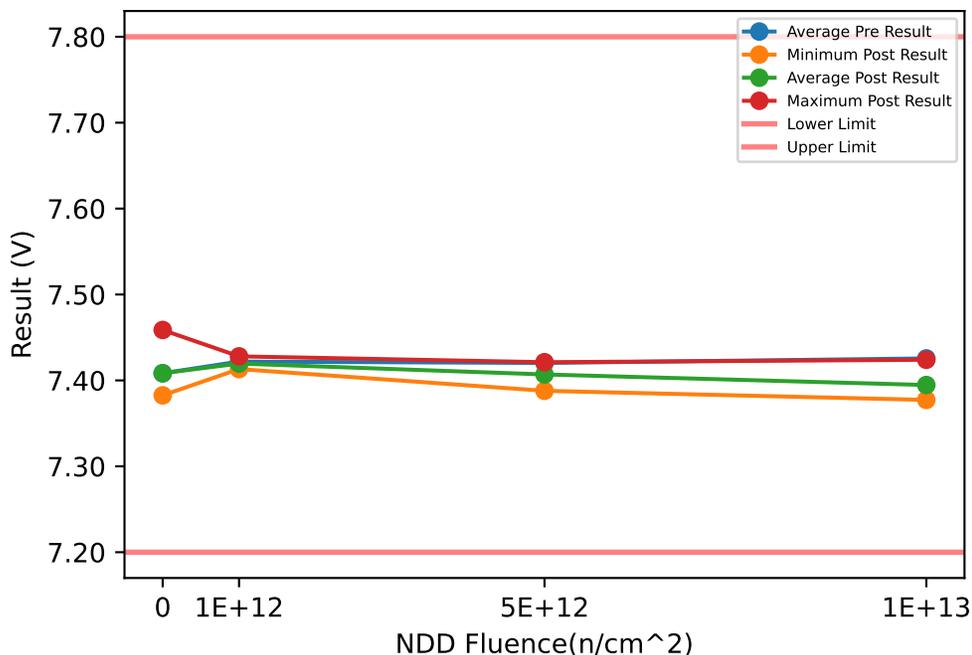
Device Test: 17.19 UVLO|PVIN_RISE/PVIN/4.5/4.5/0/1000/4.5/500kHz//@PVIN_UVLO_RISE_503X

NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 7.2, Upper Limit = 7.8 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	7.416	7.4132	-0.0028
2	1e+12	NDD	7.4305	7.428	-0.0025
3	1e+12	NDD	7.424	7.42	-0.004
4	1e+12	NDD	7.4172	7.4172	0
5	5e+12	NDD	7.4067	7.3879	-0.0188
6	5e+12	NDD	7.4293	7.416	-0.0133
7	5e+12	NDD	7.416	7.4027	-0.0133
8	5e+12	NDD	7.4293	7.4212	-0.0081
9	1e+13	NDD	7.412	7.3826	-0.0294
10	1e+13	NDD	7.4253	7.3947	-0.0306
11	1e+13	NDD	7.4092	7.3773	-0.0319
12	1e+13	NDD	7.4559	7.424	-0.0319
91	0	CORRELATION	7.3919	7.3906	-0.0013
92	0	CORRELATION	7.4574	7.4587	0.0013
93	0	CORRELATION	7.4015	7.4015	0
94	0	CORRELATION	7.3826	7.3826	0
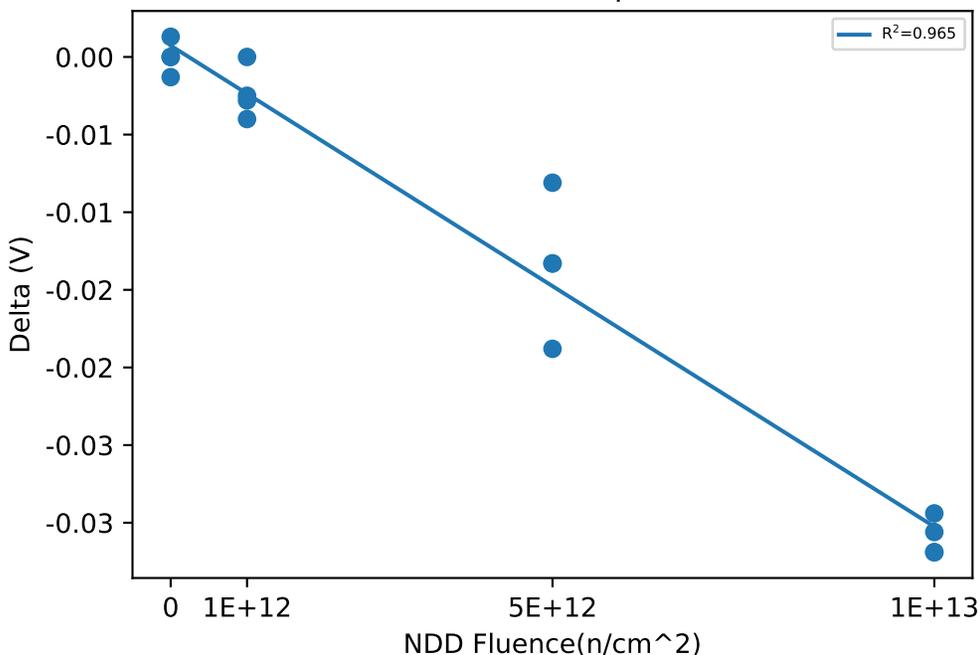
Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.3826	7.4084	7.4574	0.033598	7.3826	7.4084	7.4587	0.034449	-0.0013	2.2204e-16	0.0013	0.0010614
1e+12	7.416	7.4219	7.4305	0.0067148	7.4132	7.4196	7.428	0.0062567	-0.004	-0.002325	0	0.00168
5e+12	7.4067	7.4203	7.4293	0.011037	7.3879	7.407	7.4212	0.014899	-0.0188	-0.013375	-0.0081	0.0043691
1e+13	7.4092	7.4256	7.4559	0.021386	7.3773	7.3947	7.424	0.020878	-0.0319	-0.03095	-0.0294	0.0012014
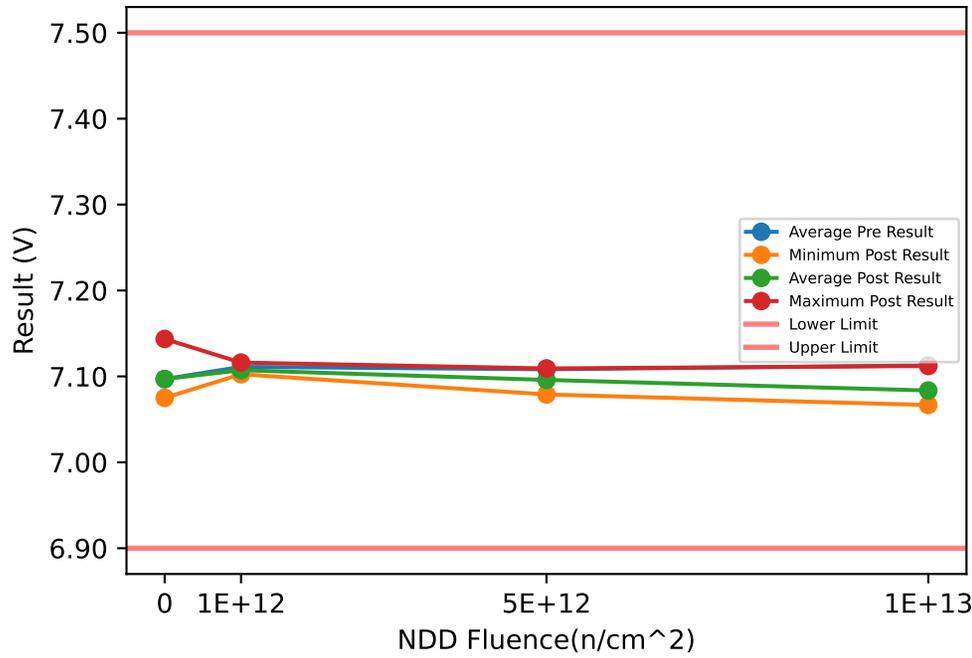
Device Test: 17.20 UVLO|PVIN_FALL/PVIN/4.5/4.5/0/1000/4.5/500kHz//@PVIN_UVLO_FALL_503X

NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 6.9, Upper Limit = 7.5 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	7.1065	7.1025	-0.004
2	1e+12	NDD	7.1189	7.1161	-0.0028
3	1e+12	NDD	7.1081	7.1065	-0.0016
4	1e+12	NDD	7.1109	7.1038	-0.0071
5	5e+12	NDD	7.097	7.079	-0.018
6	5e+12	NDD	7.1161	7.1053	-0.0108
7	5e+12	NDD	7.1038	7.0901	-0.0137
8	5e+12	NDD	7.1161	7.1093	-0.0068
9	1e+13	NDD	7.1025	7.075	-0.0275
10	1e+13	NDD	7.1093	7.0806	-0.0287
11	1e+13	NDD	7.097	7.0667	-0.0303
12	1e+13	NDD	7.1424	7.1121	-0.0303
91	0	CORRELATION	7.0818	7.0818	0
92	0	CORRELATION	7.1424	7.1436	0.0012
93	0	CORRELATION	7.0886	7.0874	-0.0012
94	0	CORRELATION	7.075	7.075	0
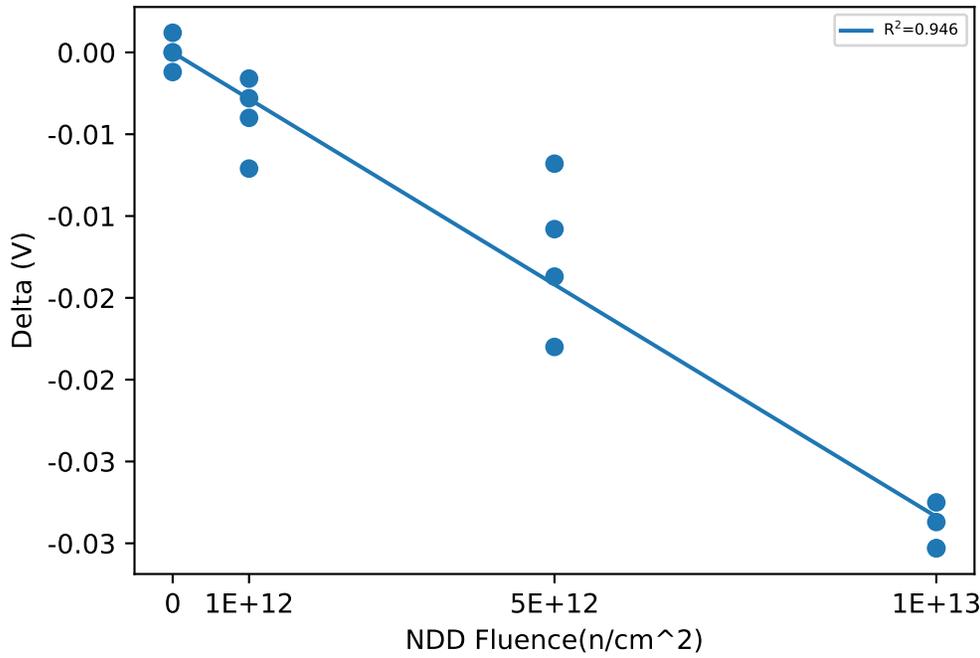
Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.075	7.0969	7.1424	0.030804	7.075	7.0969	7.1436	0.031511	-0.0012	0	0.0012	0.0009798
1e+12	7.1065	7.1111	7.1189	0.0055088	7.1025	7.1072	7.1161	0.0061467	-0.0071	-0.003875	-0.0016	0.0023627
5e+12	7.097	7.1082	7.1161	0.00948	7.079	7.0959	7.1093	0.01399	-0.018	-0.012325	-0.0068	0.004724
1e+13	7.097	7.1128	7.1424	0.020365	7.0667	7.0836	7.1121	0.01984	-0.0303	-0.0292	-0.0275	0.0013614
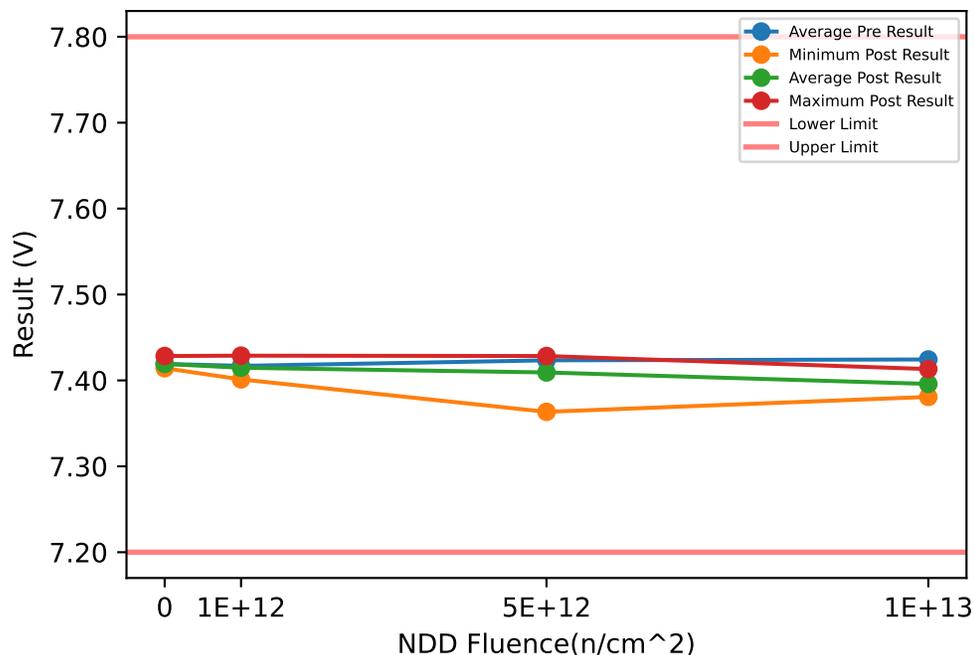
Device Test: 17.22 UVLO|VIN_RISE/VIN/4.5/4.5/0/1000/4.5/500kHz//@VIN_UVLO_RISE_503X

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 7.2, Upper Limit = 7.8 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	7.4105	7.4066	-0.0039
2	1e+12	NDD	7.4022	7.4012	-0.001
3	1e+12	NDD	7.4232	7.4222	-0.001
4	1e+12	NDD	7.4319	7.4288	-0.0031
5	5e+12	NDD	7.3815	7.3634	-0.0181
6	5e+12	NDD	7.4356	7.4221	-0.0135
7	5e+12	NDD	7.4404	7.4284	-0.012
8	5e+12	NDD	7.436	7.4232	-0.0128
9	1e+13	NDD	7.4424	7.4132	-0.0292
10	1e+13	NDD	7.4256	7.3971	-0.0285
11	1e+13	NDD	7.4101	7.3808	-0.0293
12	1e+13	NDD	7.4194	7.3926	-0.0268
91	0	CORRELATION	7.4199	7.4197	-0.0002
92	0	CORRELATION	7.4291	7.4284	-0.0007
93	0	CORRELATION	7.4145	7.4146	0.0001
94	0	CORRELATION	7.4132	7.4142	0.001
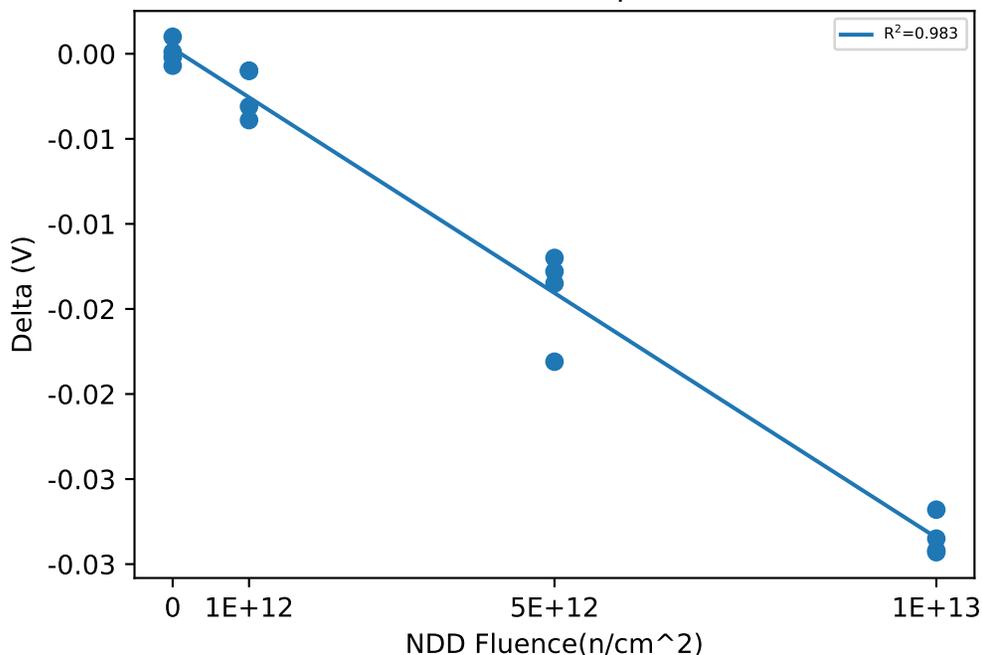
Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.4132	7.4192	7.4291	0.0072247	7.4142	7.4192	7.4284	0.0066093	-0.0007	5e-05	0.001	0.00071414
1e+12	7.4022	7.4169	7.4319	0.013187	7.4012	7.4147	7.4288	0.012948	-0.0039	-0.00225	-0.001	0.0014799
5e+12	7.3815	7.4234	7.4404	0.028001	7.3634	7.4093	7.4284	0.030707	-0.0181	-0.0141	-0.012	0.0027362
1e+13	7.4101	7.4244	7.4424	0.013601	7.3808	7.3959	7.4132	0.013412	-0.0293	-0.02845	-0.0268	0.0011561
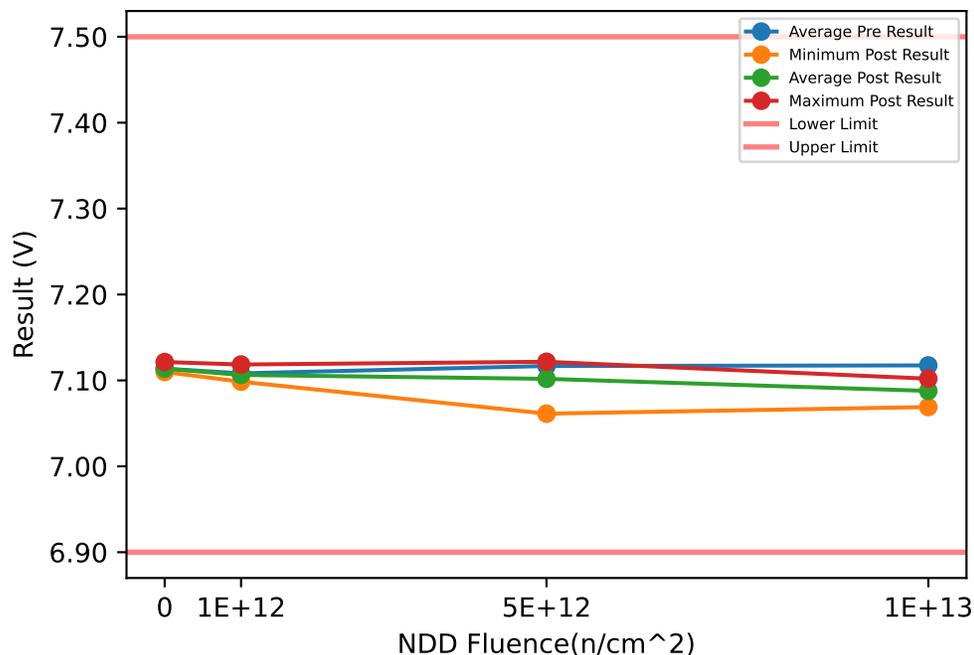
Device Test: 17.23 UVLO|VIN_FALL/VIN/4.5/4.5/0/1000/4.5/500kHz//@VIN_UVLO_FALL_503X

NDD vs Result Stats

(plot — Result (V) vs NDD Fluence(n/cm^2); legend: Average Pre Result, Minimum Post Result, Average Post Result, Maximum Post Result, Lower Limit, Upper Limit)

NDD vs Post - Pre Exposure Delta

(plot — Delta (V) vs NDD Fluence(n/cm^2); $R^2=0.951$)

Test Results (Lower Limit = 6.9, Upper Limit = 7.5 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	7.1019	7.0985	-0.0034
2	1e+12	NDD	7.1003	7.1008	0.0005
3	1e+12	NDD	7.1097	7.1076	-0.0021
4	1e+12	NDD	7.1209	7.1185	-0.0024
5	5e+12	NDD	7.0813	7.0613	-0.02
6	5e+12	NDD	7.1253	7.1114	-0.0139
7	5e+12	NDD	7.1356	7.1217	-0.0139
8	5e+12	NDD	7.1249	7.1129	-0.012
9	1e+13	NDD	7.135	7.102	-0.033
10	1e+13	NDD	7.1165	7.0908	-0.0257
11	1e+13	NDD	7.1028	7.069	-0.0338
12	1e+13	NDD	7.1156	7.0894	-0.0262
91	0	CORRELATION	7.1128	7.1098	-0.003
92	0	CORRELATION	7.1209	7.1214	0.0005
93	0	CORRELATION	7.1113	7.112	0.0007
94	0	CORRELATION	7.1099	7.1116	0.0017
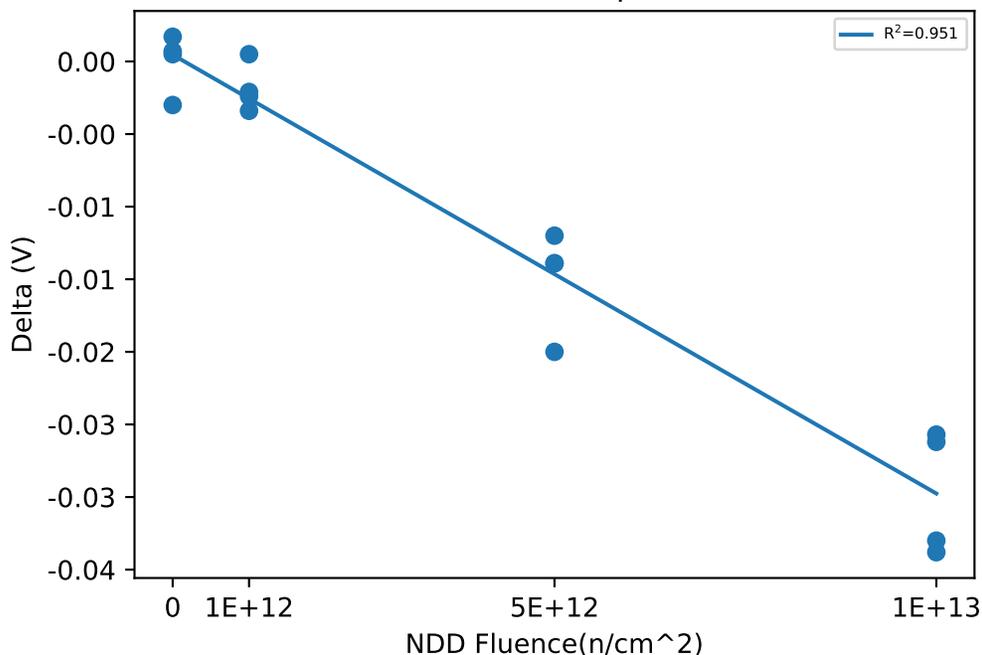
Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.1099	7.1137	7.1209	0.0049277	7.1098	7.1137	7.1214	0.0052217	-0.003	-2.5e-05	0.0017	0.0020516
1e+12	7.1003	7.1082	7.1209	0.0094099	7.0985	7.1063	7.1185	0.0089742	-0.0034	-0.00185	0.0005	0.0016623
5e+12	7.0813	7.1168	7.1356	0.024163	7.0613	7.1018	7.1217	0.027396	-0.02	-0.01495	-0.012	0.0034838
1e+13	7.1028	7.1175	7.135	0.013253	7.069	7.0878	7.102	0.013743	-0.0338	-0.029675	-0.0257	0.0043185

Device Test: 17.7 UVLO|VLDO_RISE/VLDO/4.5/4.5/0/1000/4.5/100kHz//@VLDO_UVLO_RISE

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 3.65, Upper Limit = 3.95 (V))

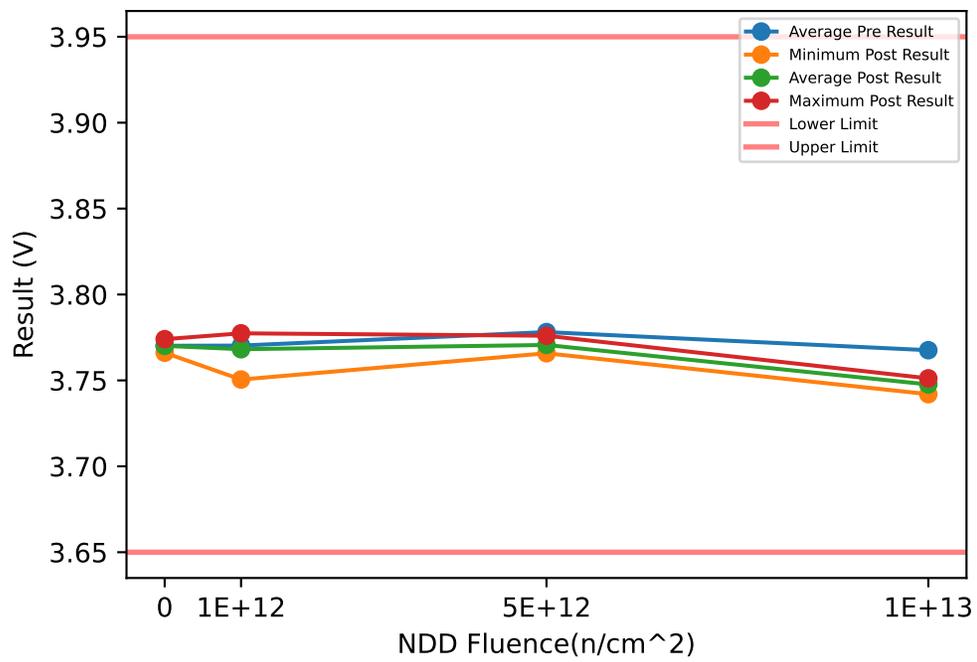| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	3.7714	3.7685	-0.0029
2	1e+12	NDD	3.7795	3.7774	-0.0021
3	1e+12	NDD	3.7777	3.7762	-0.0015
4	1e+12	NDD	3.7525	3.7505	-0.002
5	5e+12	NDD	3.783	3.776	-0.007
6	5e+12	NDD	3.7789	3.7702	-0.0087
7	5e+12	NDD	3.7787	3.7705	-0.0082
8	5e+12	NDD	3.7719	3.7658	-0.0061
9	1e+13	NDD	3.7577	3.742	-0.0157
10	1e+13	NDD	3.7698	3.7506	-0.0192
11	1e+13	NDD	3.7799	3.7512	-0.0287
12	1e+13	NDD	3.7629	3.7468	-0.0161
91	0	CORRELATION	3.7686	3.7688	0.0002
92	0	CORRELATION	3.7736	3.774	0.0004
93	0	CORRELATION	3.7721	3.7715	-0.0006
94	0	CORRELATION	3.7663	3.7661	-0.0002
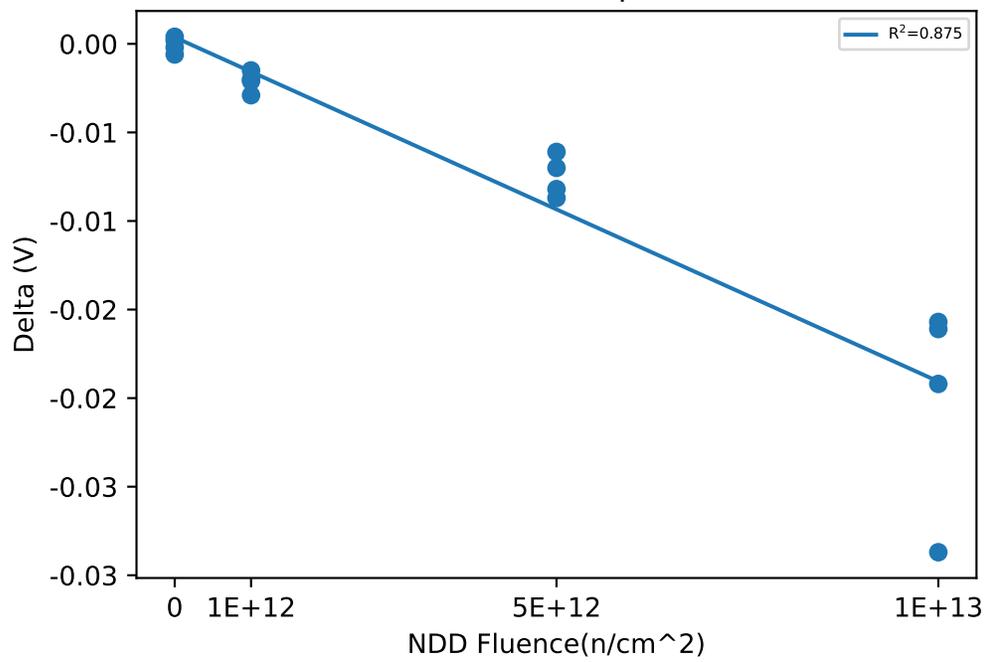
Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7663	3.7702	3.7736	0.0033131	3.7661	3.7701	3.774	0.0034088	-0.0006	-5e-05	0.0004	0.00044347
1e+12	3.7525	3.7703	3.7795	0.012348	3.7505	3.7681	3.7774	0.01241	-0.0029	-0.002125	-0.0015	0.00057951
5e+12	3.7719	3.7781	3.783	0.0045988	3.7658	3.7706	3.776	0.004178	-0.0087	-0.0075	-0.0061	0.0011747
1e+13	3.7577	3.7676	3.7799	0.0095956	3.742	3.7477	3.7512	0.0042407	-0.0287	-0.019925	-0.0157	0.0060555

Device Test: 17.8 UVLO|VLDO_FALL/VLDO/4.5/4.5/0/1000/4.5/100kHz//@VLDO_UVLO_FALL

NDD vs Result Stats

## NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 3.45, Upper Limit = 3.75 (V))

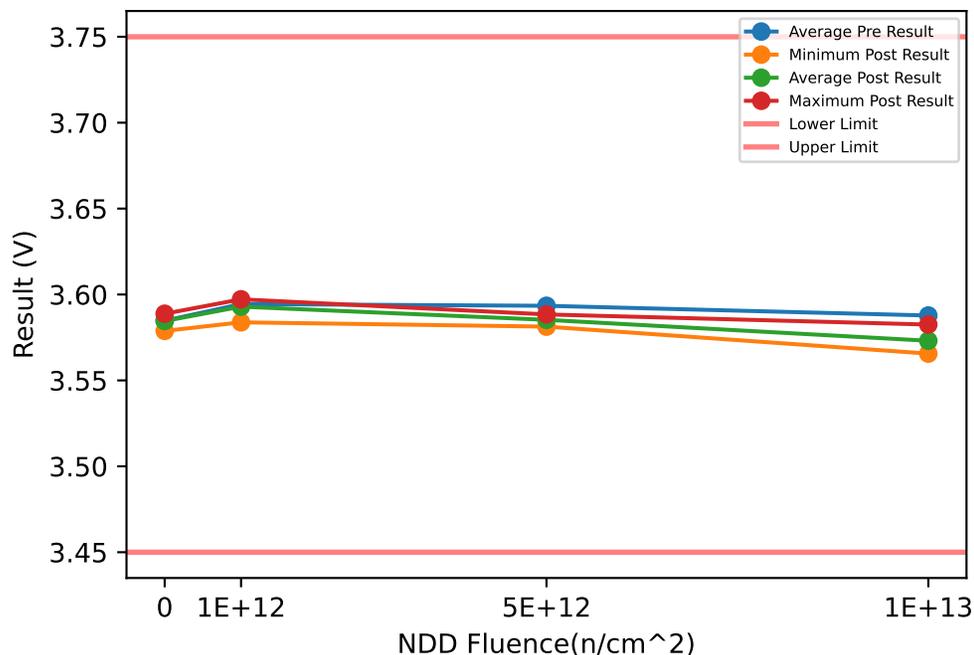| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	3.5961	3.5956	-0.0005
2	1e+12	NDD	3.5981	3.5951	-0.003
3	1e+12	NDD	3.5989	3.5972	-0.0017
4	1e+12	NDD	3.5846	3.5838	-0.0008
5	5e+12	NDD	3.5977	3.5884	-0.0093
6	5e+12	NDD	3.5916	3.5832	-0.0084
7	5e+12	NDD	3.5895	3.5813	-0.0082
8	5e+12	NDD	3.5949	3.5881	-0.0068
9	1e+13	NDD	3.5783	3.5656	-0.0127
10	1e+13	NDD	3.5856	3.5707	-0.0149
11	1e+13	NDD	3.5917	3.5735	-0.0182
12	1e+13	NDD	3.5955	3.5825	-0.013
91	0	CORRELATION	3.5846	3.5844	-0.0002
92	0	CORRELATION	3.5897	3.5888	-0.0009
93	0	CORRELATION	3.5864	3.5863	-0.0001
94	0	CORRELATION	3.5783	3.5788	0.0005
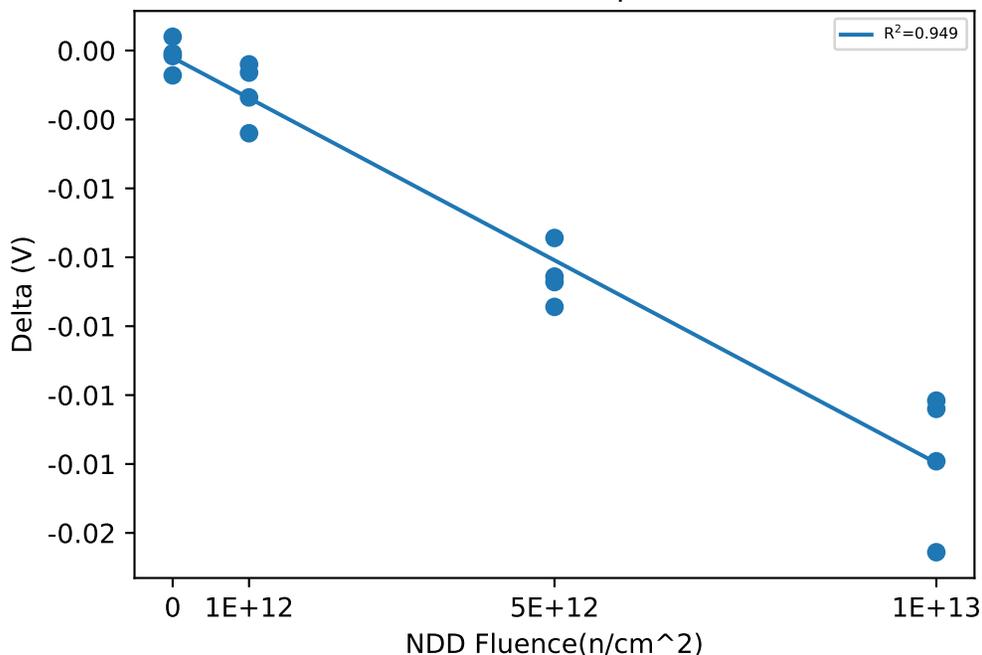
Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.5783	3.5848	3.5897	0.0047906	3.5788	3.5846	3.5888	0.0042508	-0.0009	-0.000175	0.0005	0.00057373
1e+12	3.5846	3.5944	3.5989	0.006655	3.5838	3.5929	3.5972	0.0061489	-0.003	-0.0015	-0.0005	0.0011225
5e+12	3.5895	3.5934	3.5977	0.0036142	3.5813	3.5853	3.5884	0.003552	-0.0093	-0.008175	-0.0068	0.001034
1e+13	3.5783	3.5878	3.5955	0.0075186	3.5656	3.5731	3.5825	0.0070835	-0.0182	-0.0147	-0.0127	0.0025285
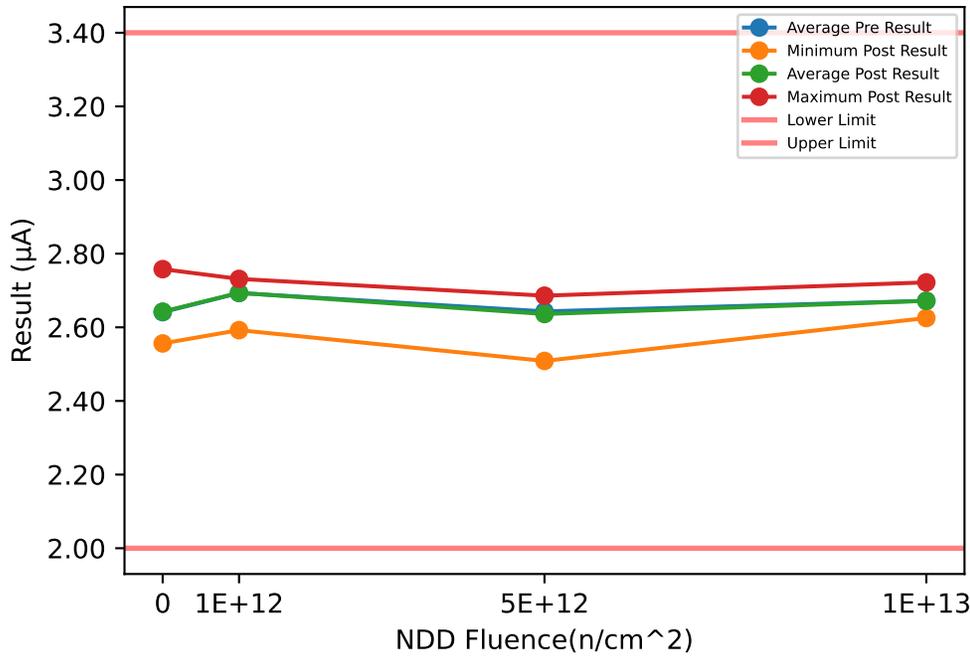
Device Test: 18.13 CURRENT|SS_0p3V/SS/14/14/0/1000/5/100kHz//@I_SS

## NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 2.0, Upper Limit = 3.4 (µA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	2.7136	2.7229	0.0093
2	1e+12	NDD	2.7292	2.7278	-0.0014
3	1e+12	NDD	2.5984	2.5923	-0.0061
4	1e+12	NDD	2.7314	2.7315	0.0001
5	5e+12	NDD	2.6787	2.671	-0.0077
6	5e+12	NDD	2.6945	2.6859	-0.0086
7	5e+12	NDD	2.516	2.5087	-0.0073
8	5e+12	NDD	2.6837	2.6787	-0.005
9	1e+13	NDD	2.7123	2.7034	-0.0089
10	1e+13	NDD	2.6247	2.6252	0.0005
11	1e+13	NDD	2.6143	2.6368	0.0225
12	1e+13	NDD	2.7363	2.722	-0.0143
91	0	CORRELATION	2.5592	2.5603	0.0011
92	0	CORRELATION	2.5559	2.5562	0.0003
93	0	CORRELATION	2.7554	2.758	0.0026
94	0	CORRELATION	2.6941	2.6958	0.0017
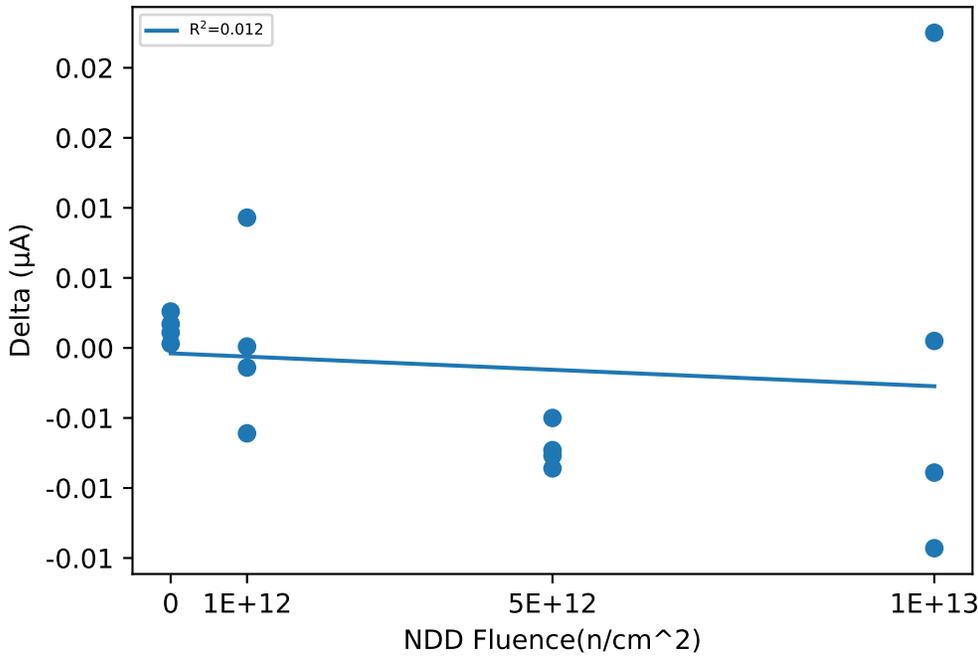
Test Statistics (µA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.5559	2.6412	2.7554	0.099733	2.5562	2.6426	2.758	0.10064	0.0003	0.001425	0.0026	0.00097082
1e+12	2.5984	2.6932	2.7314	0.063662	2.5923	2.6936	2.7315	0.067642	-0.0061	0.000475	0.0093	0.006449
5e+12	2.516	2.6432	2.6945	0.085073	2.5087	2.6361	2.6859	0.085134	-0.0086	-0.00715	-0.005	0.001533
1e+13	2.6143	2.6719	2.7363	0.061441	2.6252	2.6719	2.722	0.048011	-0.0143	-5e-05	0.0225	0.016229
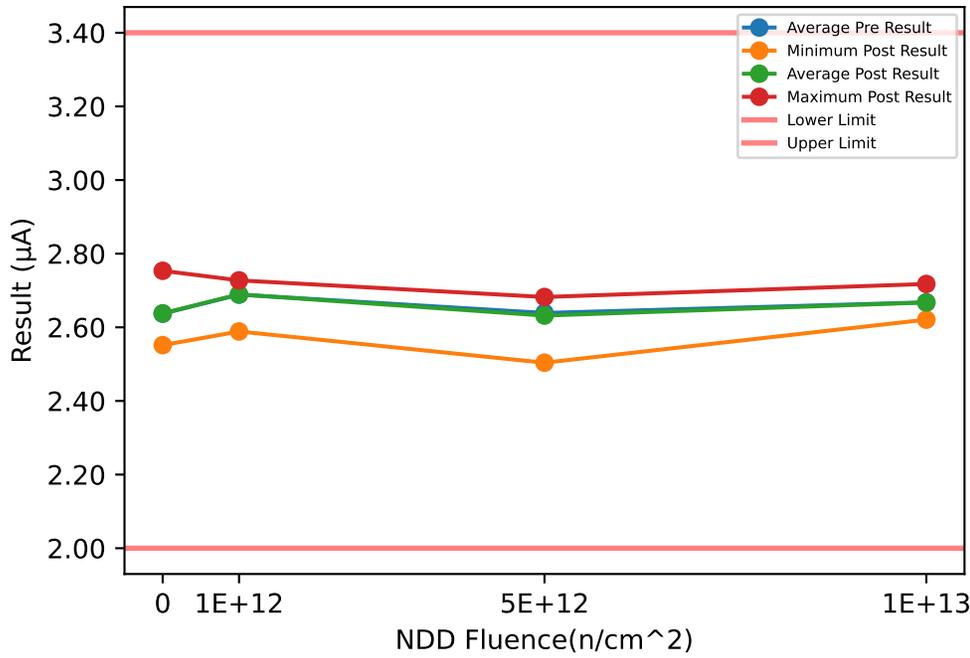
Device Test: 18.17 CURRENT|SS_0p3V/SS/12/12/0/1000/5/500kHz//@I_SS

## NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 2.0, Upper Limit = 3.4 (µA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	2.7094	2.7184	0.009
2	1e+12	NDD	2.7247	2.7232	-0.0015
3	1e+12	NDD	2.5943	2.5887	-0.0056
4	1e+12	NDD	2.7269	2.7275	0.0006
5	5e+12	NDD	2.6747	2.6663	-0.0084
6	5e+12	NDD	2.6907	2.6823	-0.0084
7	5e+12	NDD	2.5112	2.5039	-0.0073
8	5e+12	NDD	2.6793	2.6749	-0.0044
9	1e+13	NDD	2.7085	2.699	-0.0095
10	1e+13	NDD	2.6205	2.6208	0.0003
11	1e+13	NDD	2.6098	2.6324	0.0226
12	1e+13	NDD	2.7321	2.7177	-0.0144
91	0	CORRELATION	2.5553	2.5555	0.0002
92	0	CORRELATION	2.5518	2.5516	-0.0002
93	0	CORRELATION	2.7517	2.7535	0.0018
94	0	CORRELATION	2.6892	2.6914	0.0022
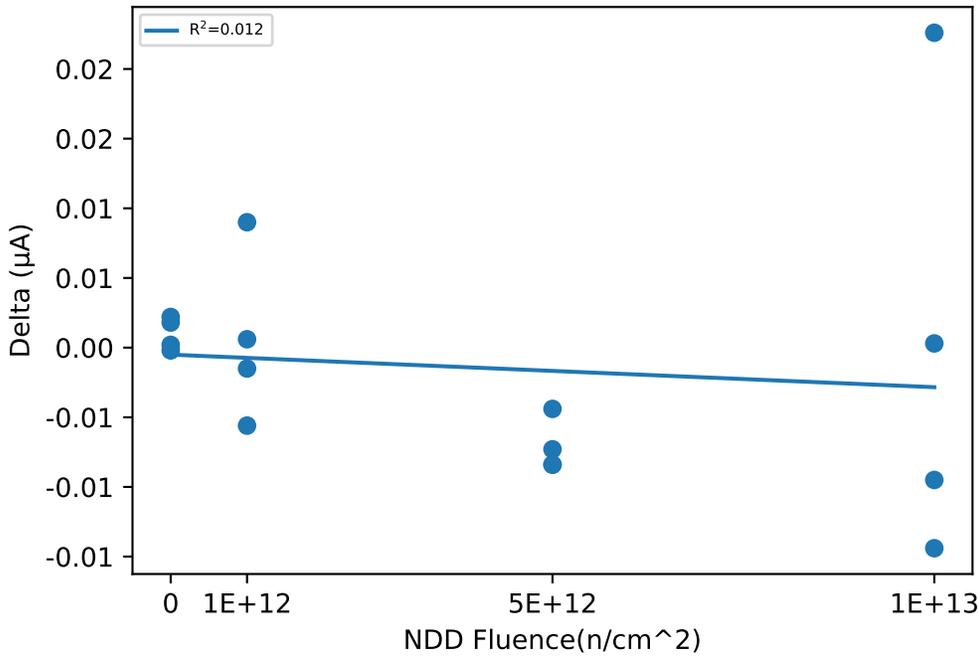
Test Statistics (µA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.5518	2.637	2.7517	0.099691	2.5516	2.638	2.7535	0.10077	-0.0002	0.001	0.0022	0.0011776
1e+12	2.5943	2.6888	2.7269	0.063495	2.5887	2.6894	2.7275	0.067269	-0.0056	0.000625	0.009	0.0061484
5e+12	2.5112	2.639	2.6907	0.085448	2.5039	2.6319	2.6823	0.08555	-0.0084	-0.007125	-0.0044	0.0018892
1e+13	2.6098	2.6677	2.7321	0.061623	2.6208	2.6675	2.7177	0.048046	-0.0144	-0.00025	0.0226	0.016414
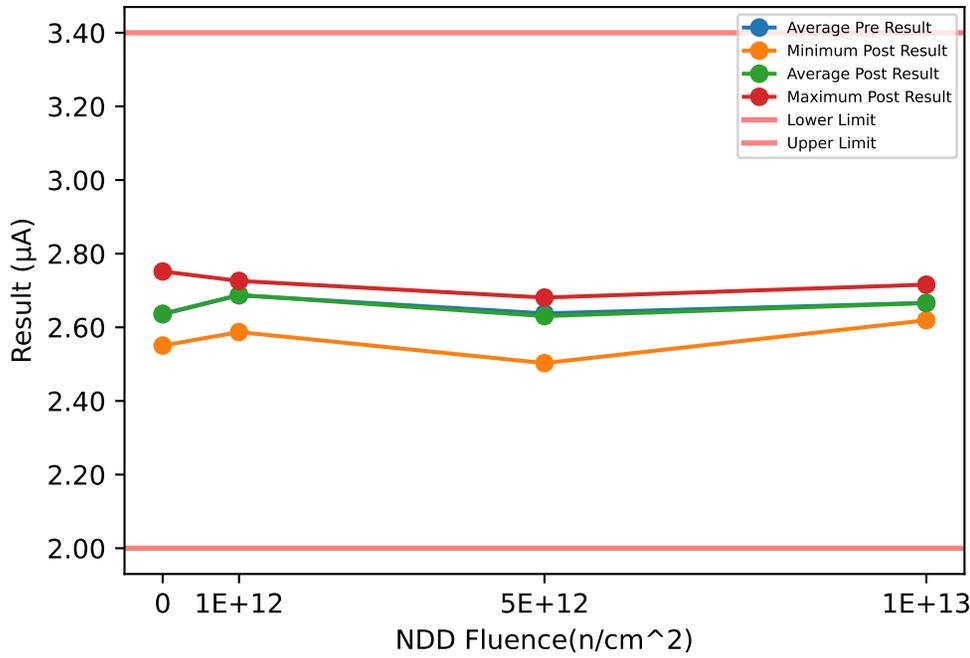
Device Test: 18.21 CURRENT|SS_0p3V/SS/14/14/0/1000/5/500kHz//@I_SS

## NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 2.0, Upper Limit = 3.4 (µA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	2.7075	2.7165	0.009
2	1e+12	NDD	2.7232	2.7219	-0.0013
3	1e+12	NDD	2.5924	2.5871	-0.0053
4	1e+12	NDD	2.7251	2.726	0.0009
5	5e+12	NDD	2.673	2.6646	-0.0084
6	5e+12	NDD	2.6897	2.6808	-0.0089
7	5e+12	NDD	2.5101	2.5028	-0.0073
8	5e+12	NDD	2.6783	2.6733	-0.005
9	1e+13	NDD	2.7068	2.6974	-0.0094
10	1e+13	NDD	2.619	2.6191	0.0001
11	1e+13	NDD	2.6083	2.6309	0.0226
12	1e+13	NDD	2.7309	2.7159	-0.015
91	0	CORRELATION	2.5535	2.5541	0.0006
92	0	CORRELATION	2.5502	2.5504	0.0002
93	0	CORRELATION	2.7503	2.7517	0.0014
94	0	CORRELATION	2.6882	2.6905	0.0023
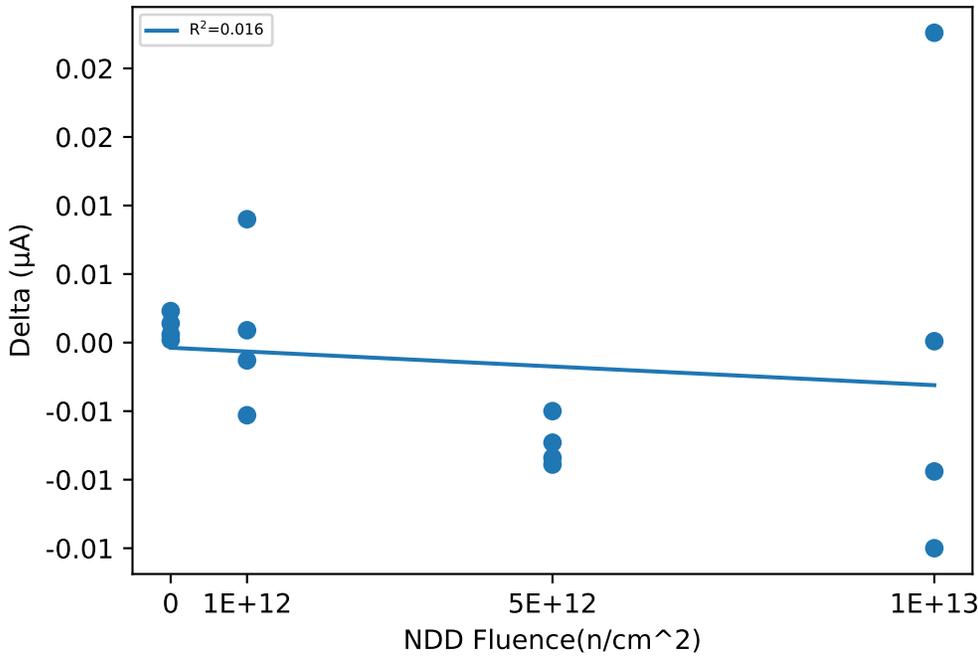
Test Statistics (µA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.5502	2.6356	2.7503	0.099927	2.5504	2.6367	2.7517	0.10065	0.0002	0.001125	0.0023	0.00092871
1e+12	2.5924	2.6871	2.7251	0.063591	2.5871	2.6879	2.726	0.067296	-0.0053	0.000825	0.009	0.006024
5e+12	2.5101	2.6378	2.6897	0.085401	2.5028	2.6304	2.6808	0.085307	-0.0089	-0.0074	-0.005	0.001734
1e+13	2.6083	2.6662	2.7309	0.061684	2.6191	2.6658	2.7159	0.047984	-0.015	-0.000425	0.0226	0.016567
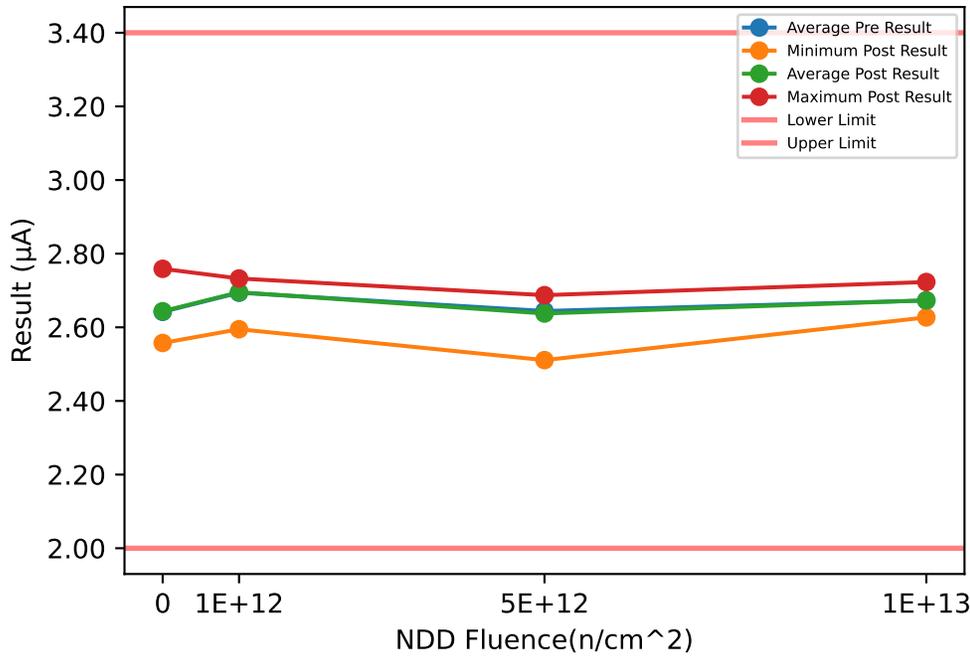
Device Test: 18.25 CURRENT|SS_0p3V/SS/8/8/0/1000/5/100kHz//@I_SS

NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 2.0, Upper Limit = 3.4 (µA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	2.7148	2.7247	0.0099
2	1e+12	NDD	2.7304	2.7291	-0.0013
3	1e+12	NDD	2.5985	2.5948	-0.0037
4	1e+12	NDD	2.7321	2.7326	0.0005
5	5e+12	NDD	2.6796	2.6723	-0.0073
6	5e+12	NDD	2.6959	2.6873	-0.0086
7	5e+12	NDD	2.5167	2.5109	-0.0058
8	5e+12	NDD	2.6849	2.6796	-0.0053
9	1e+13	NDD	2.7133	2.7047	-0.0086
10	1e+13	NDD	2.6264	2.6269	0.0005
11	1e+13	NDD	2.614	2.6379	0.0239
12	1e+13	NDD	2.7376	2.723	-0.0146
91	0	CORRELATION	2.5606	2.5613	0.0007
92	0	CORRELATION	2.557	2.5575	0.0005
93	0	CORRELATION	2.7553	2.7589	0.0036
94	0	CORRELATION	2.695	2.6971	0.0021
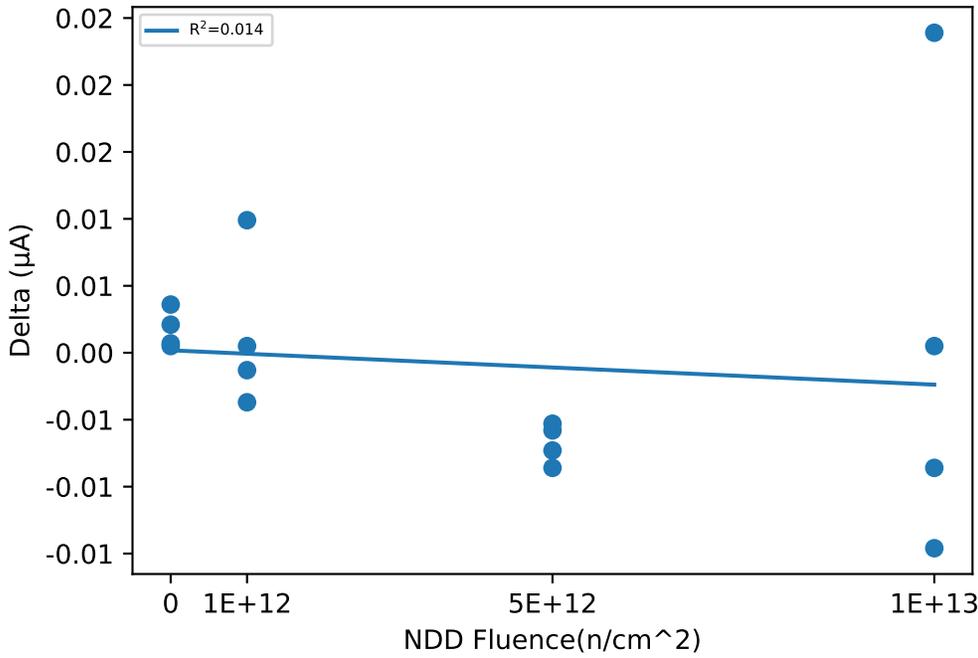
Test Statistics (µA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.557	2.642	2.7553	0.099158	2.5575	2.6437	2.7589	0.10057	0.0005	0.001725	0.0036	0.0014385
1e+12	2.5985	2.694	2.7321	0.064108	2.5948	2.6953	2.7326	0.067078	-0.0037	0.00135	0.0099	0.005954
5e+12	2.5167	2.6443	2.6959	0.085321	2.5109	2.6375	2.6873	0.084639	-0.0086	-0.00675	-0.0053	0.0014978
1e+13	2.614	2.6728	2.7376	0.061778	2.6269	2.6731	2.723	0.047826	-0.0146	0.0003	0.0239	0.016914
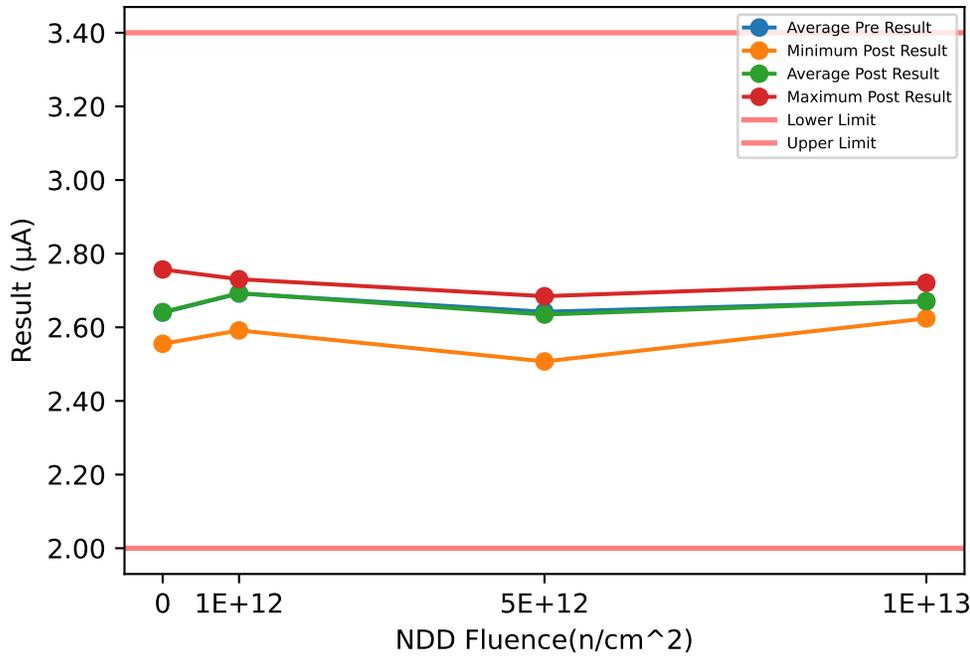
Device Test: 18.29 CURRENT|SS_0p3V/SS/8/8/0/1000/5/500kHz//@I_SS

NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 2.0, Upper Limit = 3.4 (µA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	2.7123	2.7216	0.0093
2	1e+12	NDD	2.7278	2.7271	-0.0007
3	1e+12	NDD	2.5971	2.5915	-0.0056
4	1e+12	NDD	2.7304	2.7307	0.0003
5	5e+12	NDD	2.6777	2.669	-0.0087
6	5e+12	NDD	2.6938	2.6845	-0.0093
7	5e+12	NDD	2.5149	2.5073	-0.0076
8	5e+12	NDD	2.6826	2.6773	-0.0053
9	1e+13	NDD	2.7113	2.7026	-0.0087
10	1e+13	NDD	2.6237	2.624	0.0003
11	1e+13	NDD	2.6126	2.6357	0.0231
12	1e+13	NDD	2.7353	2.7208	-0.0145
91	0	CORRELATION	2.5582	2.5588	0.0006
92	0	CORRELATION	2.5545	2.5552	0.0007
93	0	CORRELATION	2.7544	2.7571	0.0027
94	0	CORRELATION	2.6926	2.6945	0.0019
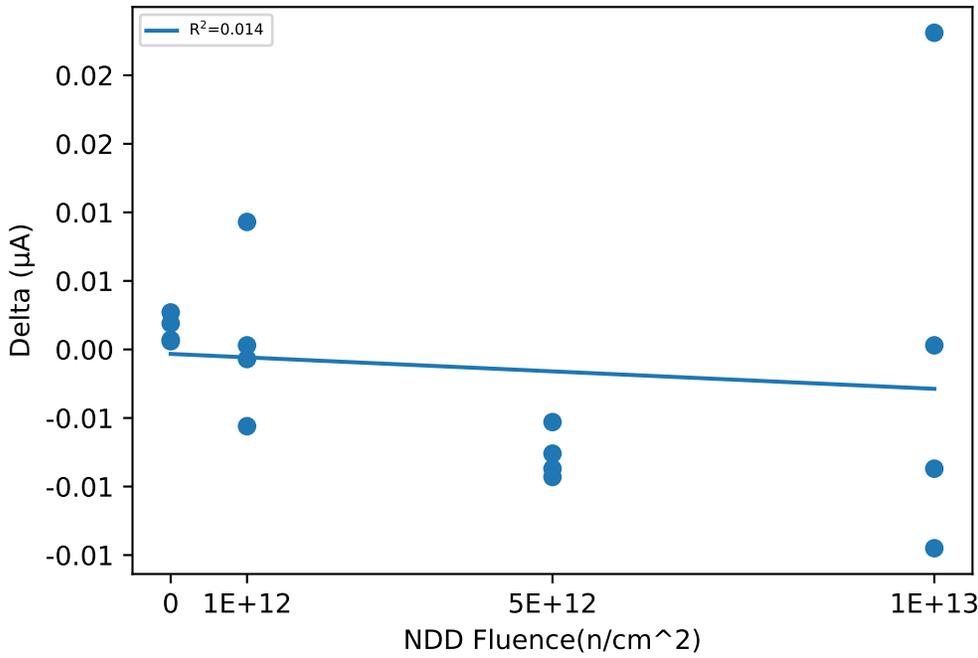
Test Statistics (µA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.5545	2.6399	2.7544	0.099759	2.5552	2.6414	2.7571	0.10076	0.0006	0.001475	0.0027	0.0010079
1e+12	2.5971	2.6919	2.7304	0.063703	2.5915	2.6927	2.7307	0.067587	-0.0056	0.000825	0.0093	0.0062104
5e+12	2.5149	2.6422	2.6938	0.085167	2.5073	2.6345	2.6845	0.085053	-0.0093	-0.007725	-0.0053	0.0017633
1e+13	2.6126	2.6707	2.7353	0.061661	2.624	2.6708	2.7208	0.048075	-0.0145	5e-05	0.0231	0.016529
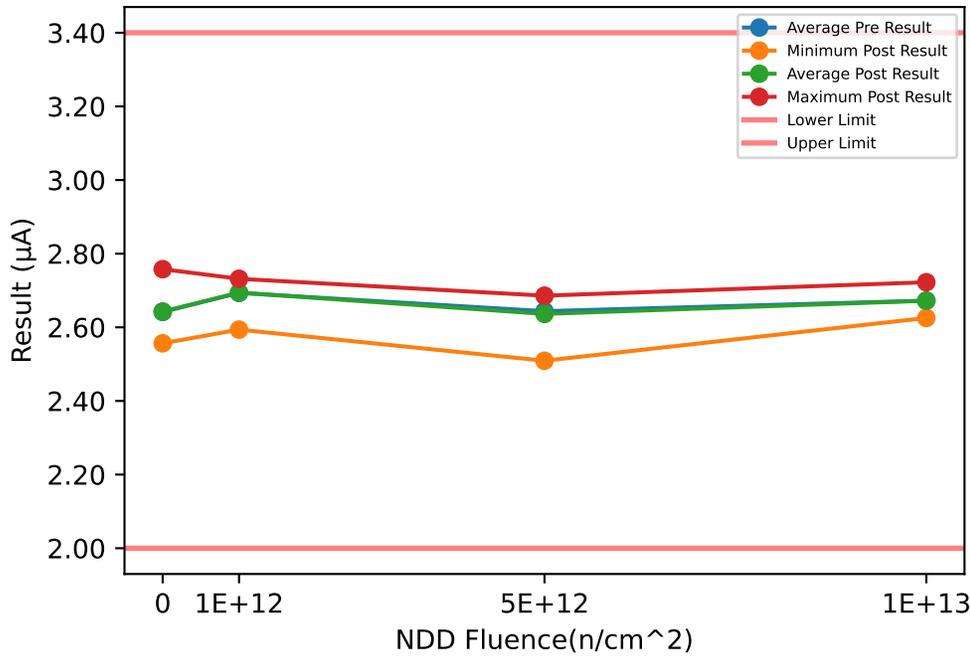
Device Test: 18.9 CURRENT|SS_0p3V/SS/12/12/0/1000/5/100kHz//@I_SS

NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 2.0, Upper Limit = 3.4 (µA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	2.7141	2.7235	0.0094
2	1e+12	NDD	2.7295	2.728	-0.0015
3	1e+12	NDD	2.5988	2.5937	-0.0051
4	1e+12	NDD	2.7314	2.7318	0.0004
5	5e+12	NDD	2.6792	2.6714	-0.0078
6	5e+12	NDD	2.6953	2.6859	-0.0094
7	5e+12	NDD	2.5164	2.5092	-0.0072
8	5e+12	NDD	2.6845	2.679	-0.0055
9	1e+13	NDD	2.713	2.7035	-0.0095
10	1e+13	NDD	2.6253	2.6254	0.0001
11	1e+13	NDD	2.6144	2.6373	0.0229
12	1e+13	NDD	2.7368	2.7224	-0.0144
91	0	CORRELATION	2.5601	2.5606	0.0005
92	0	CORRELATION	2.5562	2.5565	0.0003
93	0	CORRELATION	2.7559	2.7579	0.002
94	0	CORRELATION	2.6944	2.6964	0.002
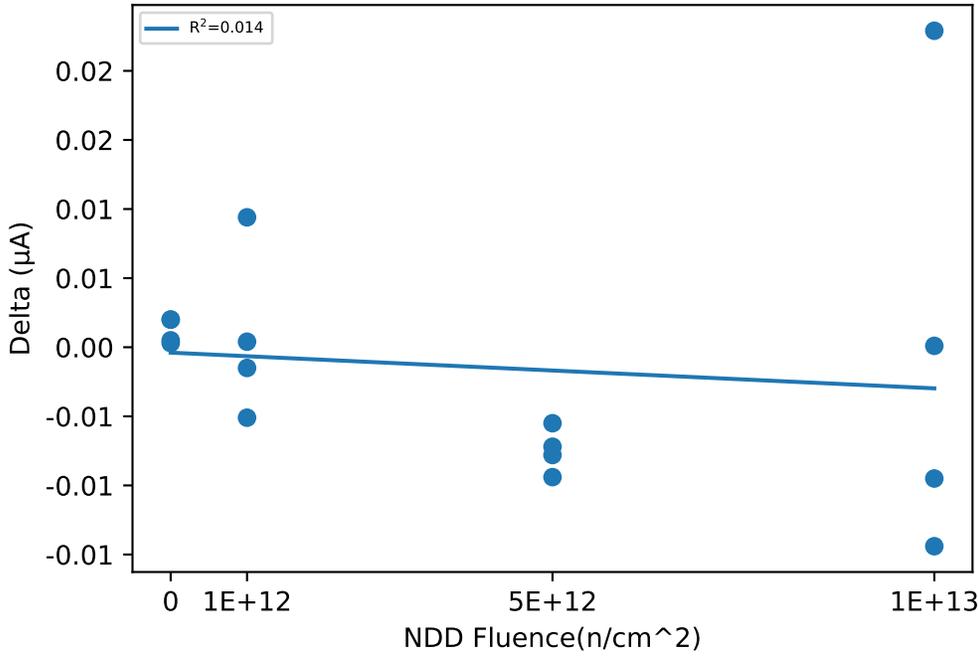
Test Statistics (µA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.5562	2.6416	2.7559	0.099646	2.5565	2.6429	2.7579	0.10054	0.0003	0.0012	0.002	0.00092736
1e+12	2.5988	2.6934	2.7314	0.063574	2.5937	2.6943	2.7318	0.067119	-0.0051	0.0008	0.0094	0.0061704
5e+12	2.5164	2.6439	2.6953	0.08523	2.5092	2.6364	2.6859	0.08499	-0.0094	-0.007475	-0.0055	0.0016112
1e+13	2.6144	2.6724	2.7368	0.061585	2.6254	2.6722	2.7224	0.047986	-0.0144	-0.000225	0.0229	0.016551

Device Test: 19.10 CURRENT|EA_SOURCE//12/12/0/0/5/500kHz//@EA_I_SOURCE

NDD vs Result Stats

Legend:
- Average Pre Result
- Minimum Post Result
- Average Post Result
- Maximum Post Result
- Lower Limit
- Upper Limit

NDD vs Post - Pre Exposure Delta

R^2=0.793

Test Results (Lower Limit = 95.0, Upper Limit = 210.0 (µA))

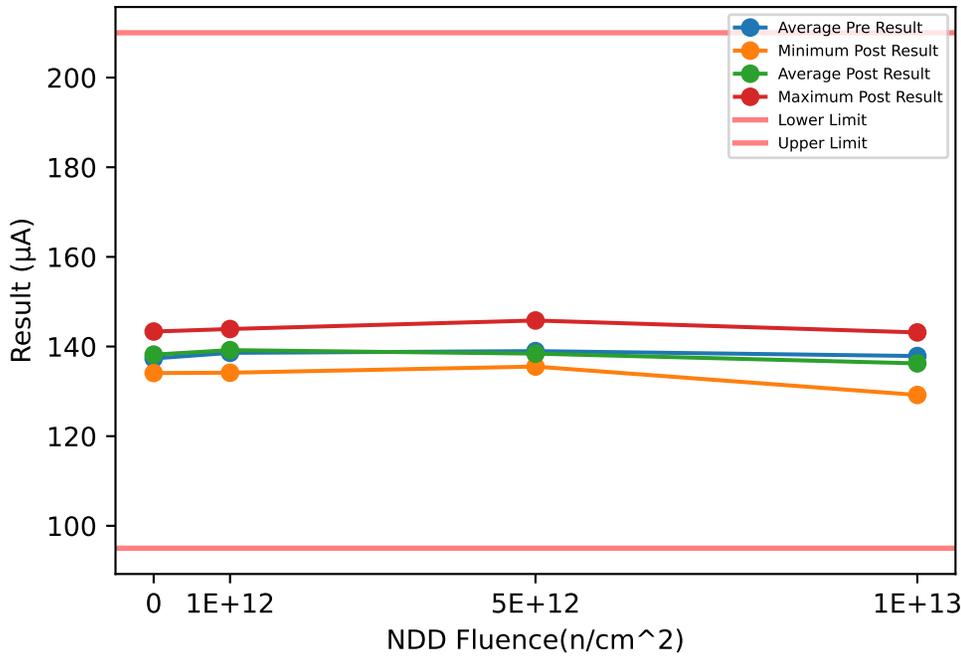| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	133.45	134.16	0.7052
2	1e+12	NDD	134.76	135.25	0.4943
3	1e+12	NDD	142.85	143.91	1.0524
4	1e+12	NDD	143.29	143.48	0.1836
5	5e+12	NDD	135.75	135.67	-0.0811
6	5e+12	NDD	145.91	145.81	-0.102
7	5e+12	NDD	137.85	136.65	-1.1991
8	5e+12	NDD	136.41	135.53	-0.8814
9	1e+13	NDD	145.68	143.14	-2.5358
10	1e+13	NDD	132.68	131.73	-0.9455
11	1e+13	NDD	129.97	129.2	-0.7726
12	1e+13	NDD	143.2	140.9	-2.2977
91	0	CORRELATION	135.75	136.26	0.5158
92	0	CORRELATION	133.18	134.09	0.9072
93	0	CORRELATION	142.19	143.34	1.1482
94	0	CORRELATION	138.23	139.08	0.8452
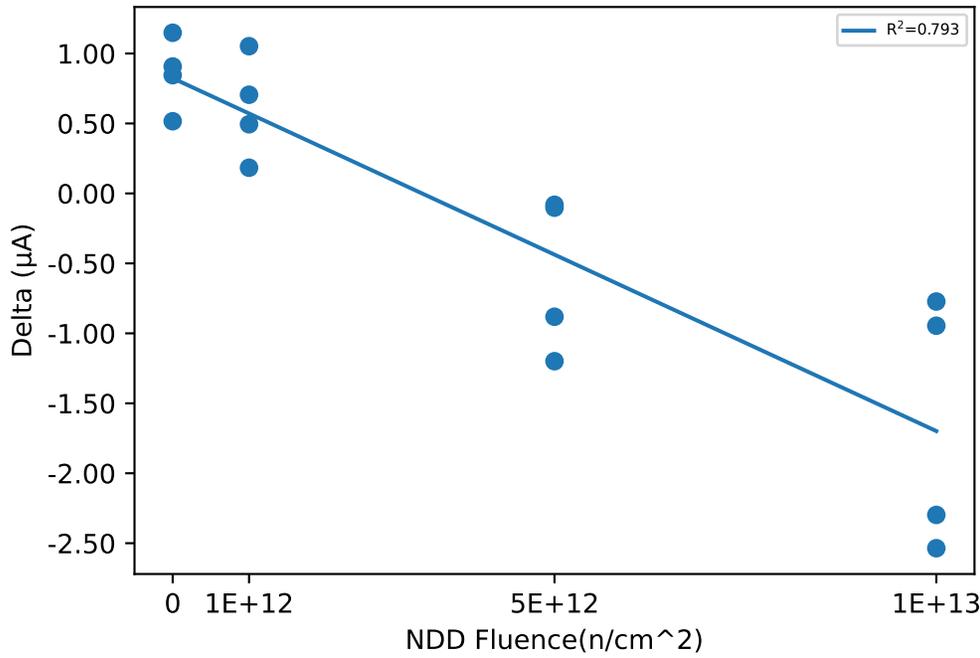
Test Statistics (µA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	133.18	137.34	142.19	3.838	134.09	138.19	143.34	3.9945	0.5158	0.8541	1.1482	0.26067
1e+12	133.45	138.59	143.29	5.2084	134.16	139.2	143.91	5.2107	0.1836	0.60888	1.0524	0.36514
5e+12	135.75	138.98	145.91	4.7035	135.53	138.41	145.81	4.9555	-1.1991	-0.5659	-0.0811	0.56294
1e+13	129.97	137.88	145.68	7.7188	129.2	136.24	143.14	6.814	-2.5358	-1.6379	-0.7726	0.90733
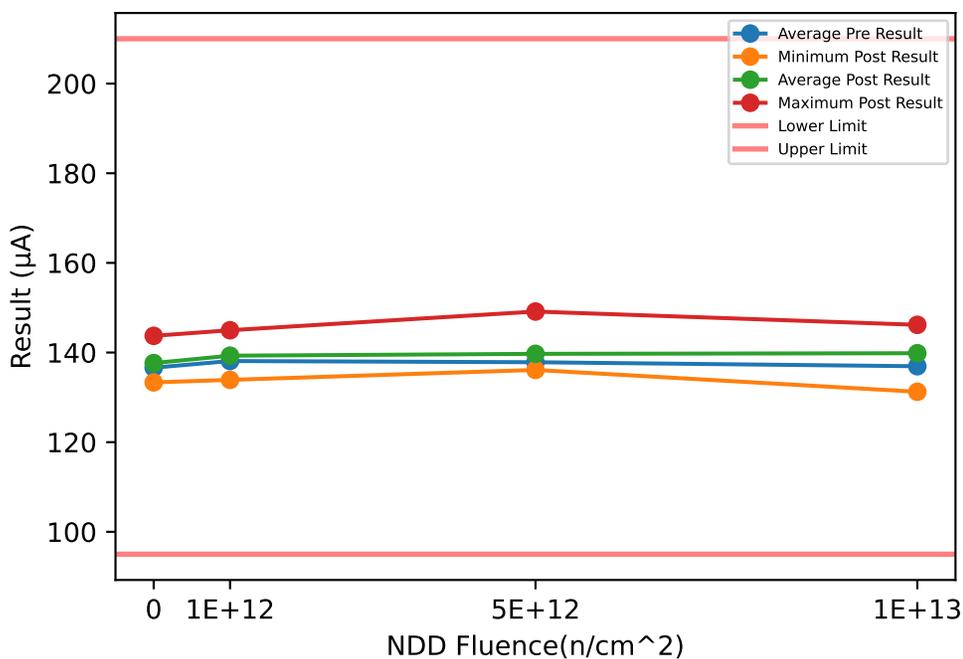
Device Test: 19.11 CURRENT|EA_SINK//12/12/0/0/5/500kHz//@EA_I_SINK

## NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 95.0, Upper Limit = 210.0 (µA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	132.65	133.9	1.2506
2	1e+12	NDD	134.41	135.57	1.1536
3	1e+12	NDD	141.65	142.75	1.0965
4	1e+12	NDD	143.71	144.97	1.2666
5	5e+12	NDD	134.28	136.69	2.4122
6	5e+12	NDD	146.61	149.14	2.5341
7	5e+12	NDD	135.26	136.12	0.8595
8	5e+12	NDD	135.19	136.87	1.6784
9	1e+13	NDD	143.74	146.18	2.4393
10	1e+13	NDD	132.74	136.26	3.515
11	1e+13	NDD	127.6	131.25	3.6427
12	1e+13	NDD	143.67	145.69	2.0203
91	0	CORRELATION	134.44	135.5	1.0613
92	0	CORRELATION	132.4	133.34	0.9391
93	0	CORRELATION	142.57	143.72	1.1571
94	0	CORRELATION	137.08	138.03	0.9553
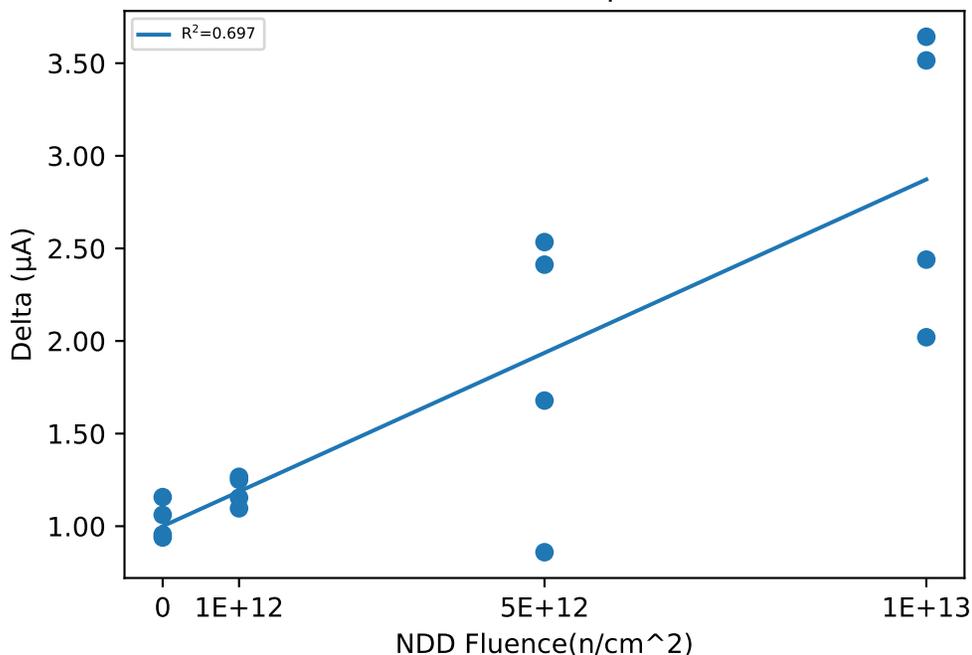
Test Statistics (µA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	132.4	136.62	142.57	4.4031	133.34	137.65	143.72	4.4821	0.9391	1.0282	1.1571	0.10159
1e+12	132.65	138.1	143.71	5.3967	133.9	139.3	144.97	5.3912	1.0965	1.1918	1.2666	0.080816
5e+12	134.28	137.83	146.61	5.8657	136.12	139.71	149.14	6.299	0.8595	1.871	2.5341	0.77305
1e+13	127.6	136.94	143.74	8.0912	131.25	139.84	146.18	7.3296	2.0203	2.9043	3.6427	0.79914

Device Test: 19.12 CURRENT|EA//12/12/0/0/5/500kHz//@EA_IB

NDD vs Result Stats
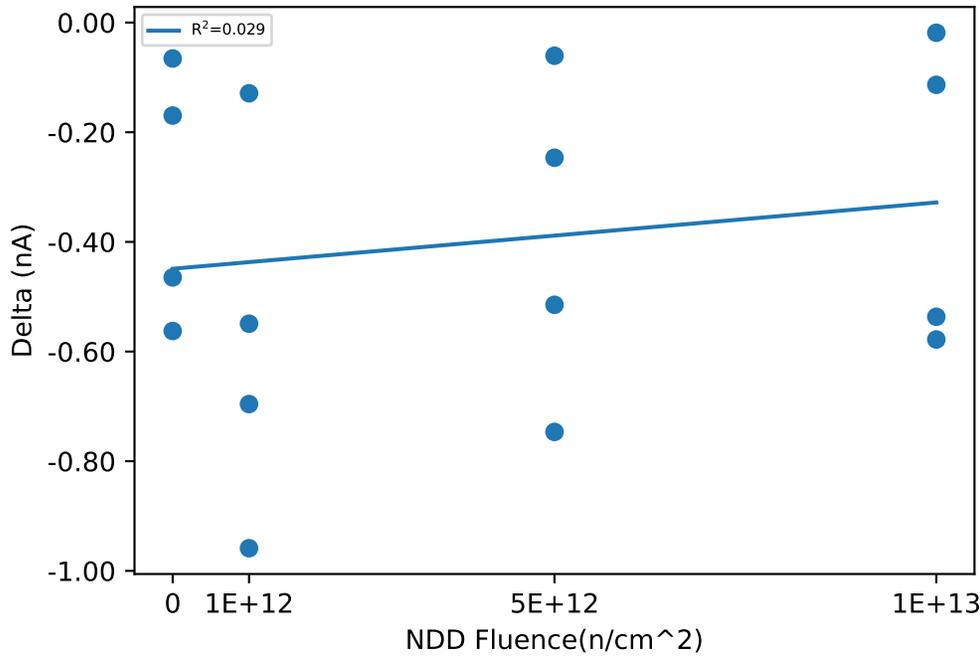
NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 25.0 (nA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.312	-0.6467	-0.9587
2	1e+12	NDD	0.0187	-0.6771	-0.6958
3	1e+12	NDD	-0.0999	-0.6491	-0.5492
4	1e+12	NDD	-0.4795	-0.6085	-0.129
5	5e+12	NDD	0.0312	-0.7154	-0.7466
6	5e+12	NDD	-0.1936	-0.7083	-0.5147
7	5e+12	NDD	-0.412	-0.6585	-0.2465
8	5e+12	NDD	-0.5449	-0.6054	-0.0605
9	1e+13	NDD	0.0094	-0.5686	-0.578
10	1e+13	NDD	-0.0781	-0.6147	-0.5366
11	1e+13	NDD	-0.5681	-0.5867	-0.0186
12	1e+13	NDD	-0.5044	-0.6179	-0.1135
91	0	CORRELATION	-0.0811	-0.6436	-0.5625
92	0	CORRELATION	-0.1374	-0.6022	-0.4648
93	0	CORRELATION	-0.6804	-0.7459	-0.0655
94	0	CORRELATION	-0.4888	-0.6584	-0.1696

Test Statistics (nA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.6804	-0.34693	-0.0811	0.2863	-0.7459	-0.66253	-0.6022	0.060458	-0.5625	-0.3156	-0.0655	0.236
1e+12	-0.4795	-0.062175	0.312	0.32768	-0.6771	-0.64535	-0.6085	0.028177	-0.9587	-0.58318	-0.129	0.34695
5e+12	-0.5449	-0.27982	0.0312	0.25292	-0.7154	-0.6719	-0.6054	0.051052	-0.7466	-0.39208	-0.0605	0.30103
1e+13	-0.5681	-0.2853	0.0094	0.29312	-0.6179	-0.59698	-0.5686	0.023542	-0.578	-0.31167	-0.0186	0.28676

Device Test: 19.13 LEVEL|TRANSCONDUCTANCE//14/14/0/0/5/500kHz//@EA_GM

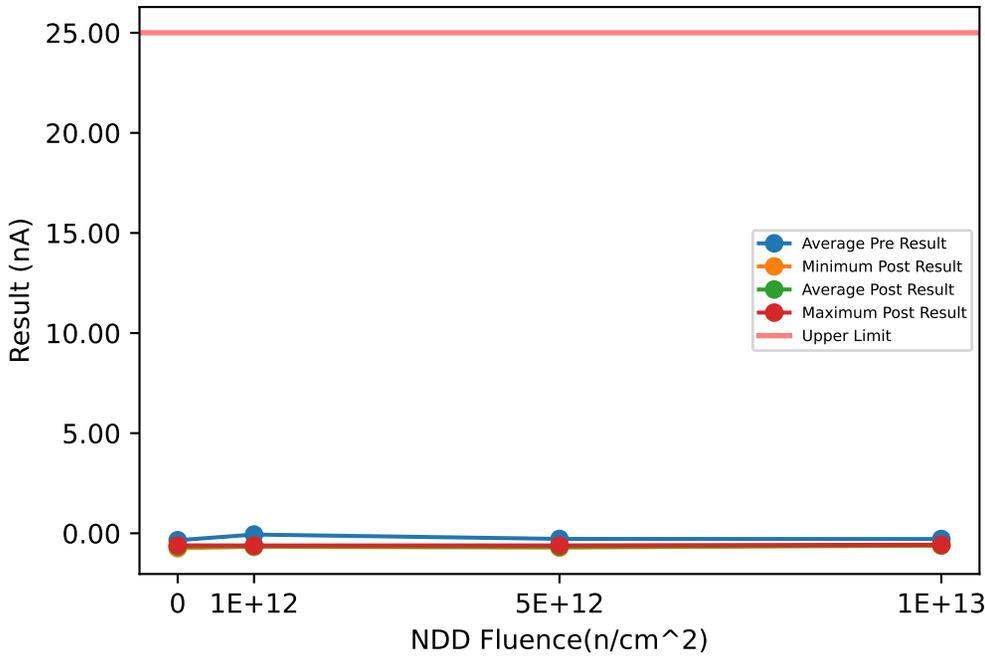## NDD vs Result Stats
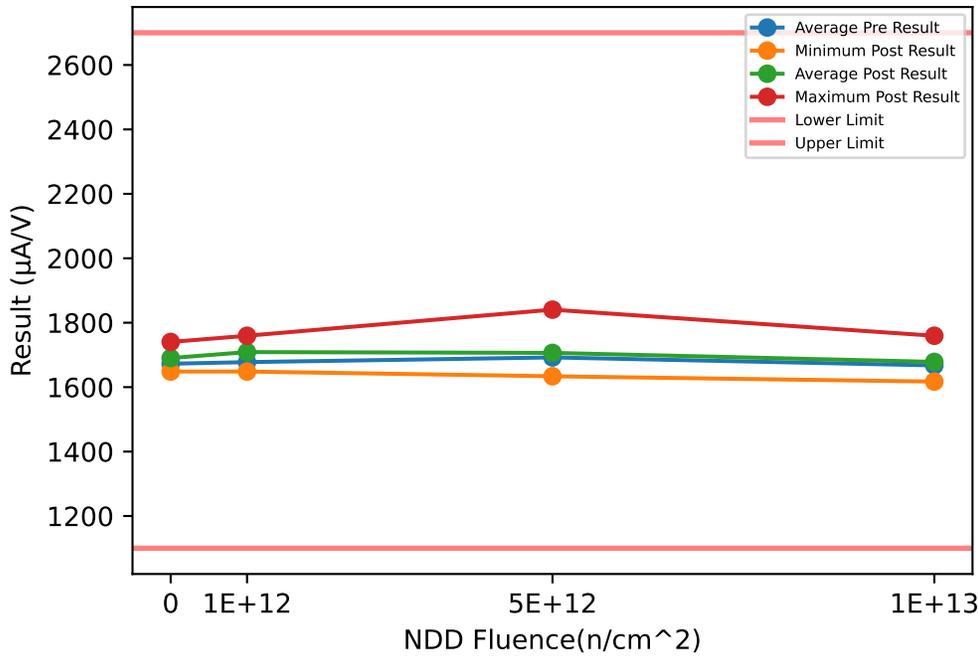
NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 1100.0, Upper Limit = 2700.0 (µA/V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1633.7	1648.5	14.824
2	1e+12	NDD	1633.8	1668	34.127
3	1e+12	NDD	1703.7	1759.4	55.726
4	1e+12	NDD	1739.4	1759.5	20.085
5	5e+12	NDD	1617.2	1665.7	48.503
6	5e+12	NDD	1799.1	1840.5	41.456
7	5e+12	NDD	1685.8	1633.8	-52.014
8	5e+12	NDD	1667	1685.4	18.463
9	1e+13	NDD	1759.3	1719.4	-39.937
10	1e+13	NDD	1601.2	1617.4	16.254
11	1e+13	NDD	1570.1	1617.2	47.16
12	1e+13	NDD	1739.4	1759.5	20.085
91	0	CORRELATION	1650.5	1648.5	-2.0109
92	0	CORRELATION	1633.8	1650.8	16.928
93	0	CORRELATION	1722	1740.3	18.282
94	0	CORRELATION	1684.5	1721.7	37.174
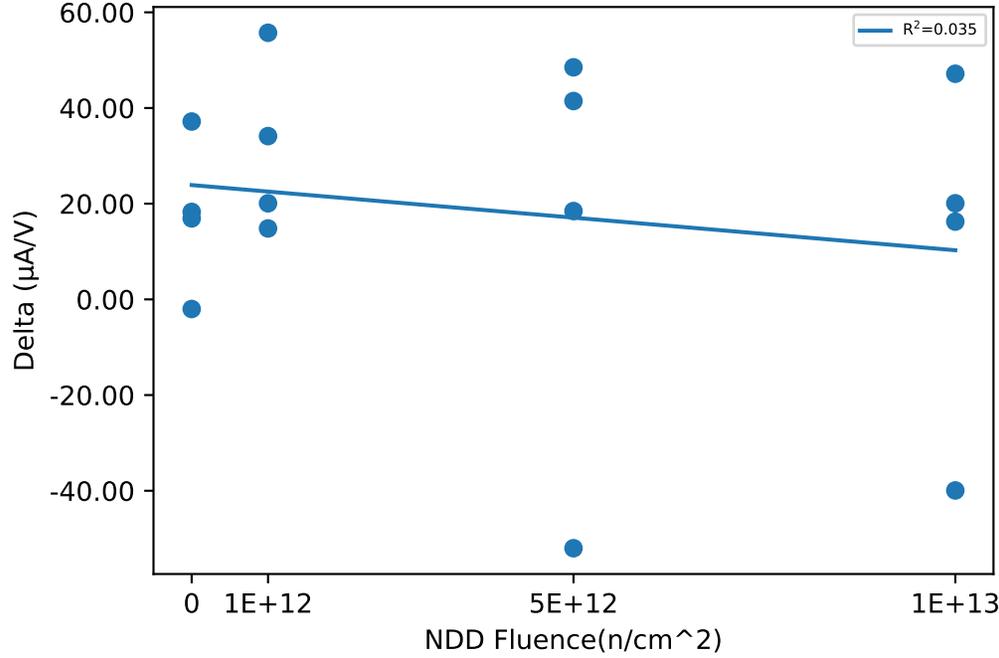
Test Statistics (µA/V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1633.8	1672.7	1722	39.053	1648.5	1690.3	1740.3	47.599	-2.0109	17.593	37.174	16.007
1e+12	1633.7	1677.7	1739.4	52.759	1648.5	1708.8	1759.5	58.996	14.824	31.191	55.726	18.274
5e+12	1617.2	1692.2	1799.1	76.873	1633.8	1706.3	1840.5	91.948	-52.014	14.102	48.503	45.906
1e+13	1570.1	1667.5	1759.3	95.736	1617.2	1678.4	1759.5	72.386	-39.937	10.891	47.16	36.57

Device Test: 19.14 CURRENT|EA_SOURCE//14/14/0/0/5/500kHz//@EA_I_SOURCE

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 95.0, Upper Limit = 210.0 (µA))

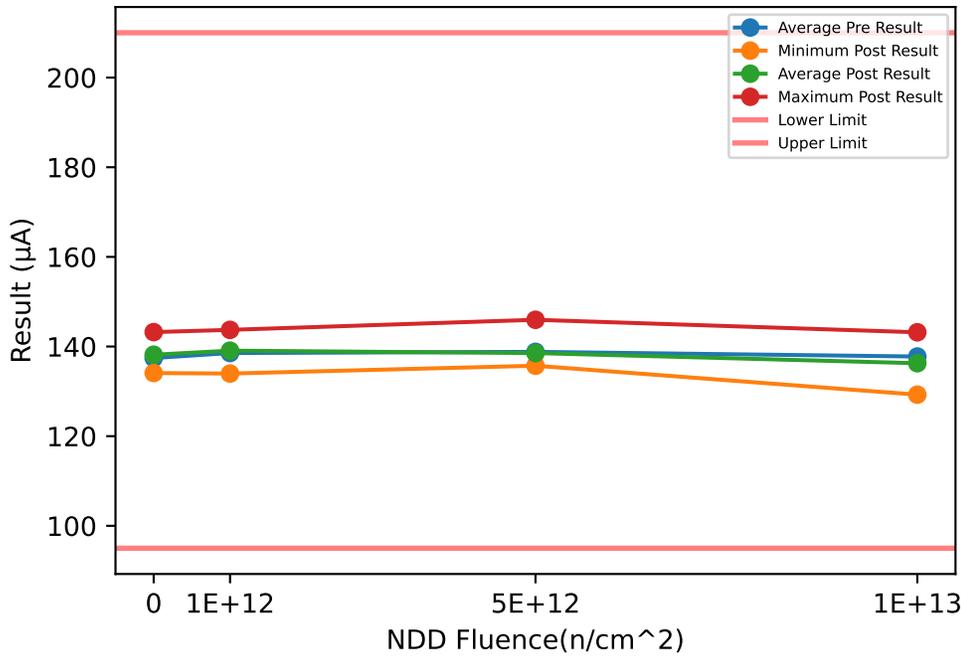| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	133.49	133.97	0.4853
2	1e+12	NDD	134.85	135.25	0.3998
3	1e+12	NDD	142.95	143.72	0.7693
4	1e+12	NDD	142.92	143.38	0.4663
5	5e+12	NDD	135.62	135.73	0.1074
6	5e+12	NDD	145.88	145.97	0.0866
7	5e+12	NDD	137.66	136.74	-0.9158
8	5e+12	NDD	136.1	135.72	-0.3788
9	1e+13	NDD	145.77	143.17	-2.5986
10	1e+13	NDD	132.61	131.64	-0.9767
11	1e+13	NDD	129.62	129.26	-0.3632
12	1e+13	NDD	143.07	141.03	-2.0463
91	0	CORRELATION	135.69	136.42	0.7356
92	0	CORRELATION	133.18	134.09	0.9072
93	0	CORRELATION	142.63	143.22	0.5815
94	0	CORRELATION	138.23	138.95	0.7195
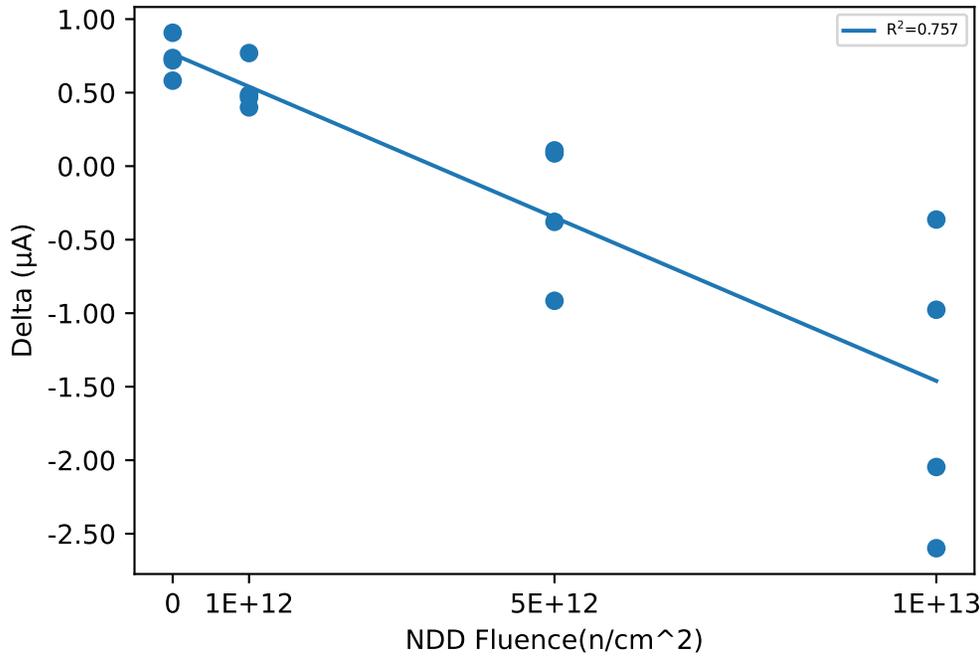
Test Statistics (µA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	133.18	137.43	142.63	4.0346	134.09	138.17	143.22	3.9072	0.5815	0.73595	0.9072	0.13348
1e+12	133.49	138.55	142.95	5.0909	133.97	139.08	143.72	5.1896	0.3998	0.53018	0.7693	0.16358
5e+12	135.62	138.81	145.88	4.7898	135.72	138.54	145.97	4.9746	-0.9158	-0.27515	0.1074	0.48249
1e+13	129.62	137.77	145.77	7.8551	129.26	136.27	143.17	6.8529	-2.5986	-1.4962	-0.3632	1.0118
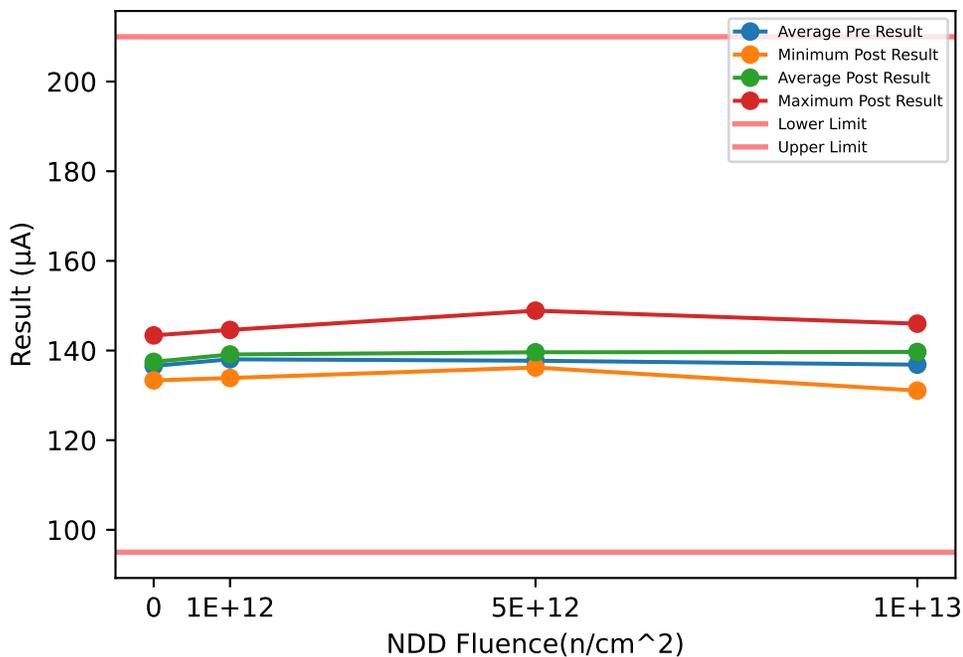
Device Test: 19.15 CURRENT|EA_SINK//14/14/0/0/5/500kHz//@EA_I_SINK

NDD vs Result Stats

Legend:
- Average Pre Result
- Minimum Post Result
- Average Post Result
- Maximum Post Result
- Lower Limit
- Upper Limit

NDD vs Post - Pre Exposure Delta

$R^2=0.699$

Test Results (Lower Limit = 95.0, Upper Limit = 210.0 (μA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	132.27	133.87	1.5963
2	1e+12	NDD	134.07	135.35	1.2802
3	1e+12	NDD	141.94	142.69	0.7501
4	1e+12	NDD	143.89	144.6	0.7012
5	5e+12	NDD	134.28	136.66	2.3808
6	5e+12	NDD	146.29	148.89	2.5979
7	5e+12	NDD	135.29	136.21	0.9223
8	5e+12	NDD	135.03	136.68	1.647
9	1e+13	NDD	143.74	145.99	2.2508
10	1e+13	NDD	132.36	136.07	3.7046
11	1e+13	NDD	127.86	131.06	3.2021
12	1e+13	NDD	143.42	145.63	2.2089
91	0	CORRELATION	134.38	135.5	1.1242
92	0	CORRELATION	132.59	133.34	0.75
93	0	CORRELATION	142.35	143.38	1.0319
94	0	CORRELATION	136.98	137.69	0.704
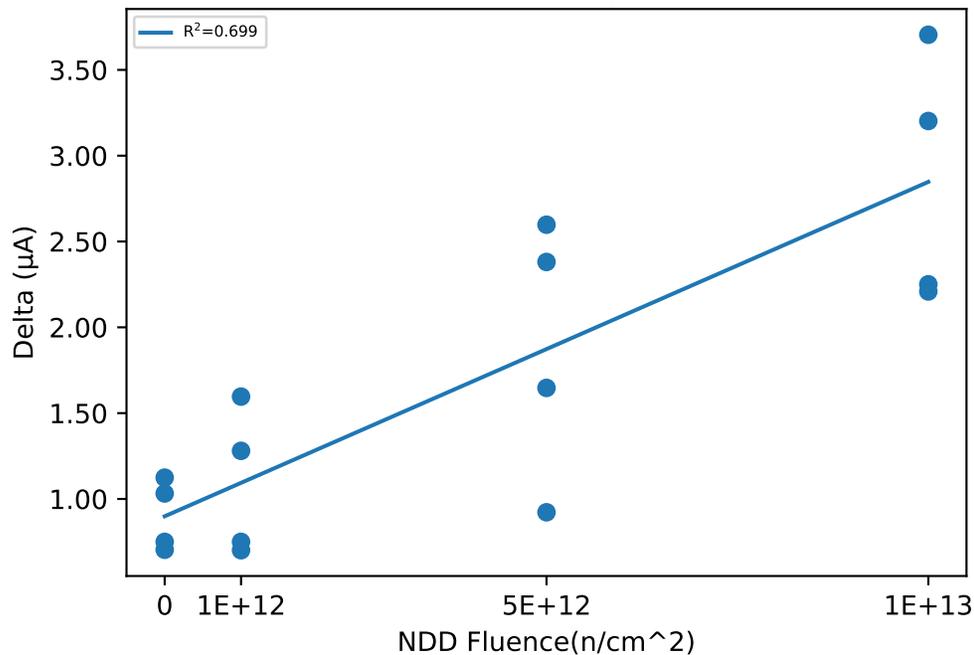
Test Statistics (μA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	132.59	136.57	142.35	4.2512	133.34	137.47	143.38	4.3174	0.704	0.90253	1.1242	0.20701
1e+12	132.27	138.04	143.89	5.7311	133.87	139.12	144.6	5.3085	0.7012	1.0819	1.5963	0.43165
5e+12	134.28	137.72	146.29	5.7281	136.21	139.61	148.89	6.1899	0.9223	1.887	2.5979	0.76102
1e+13	127.86	136.85	143.74	7.9941	131.06	139.69	145.99	7.3633	2.2089	2.8416	3.7046	0.73577

Device Test: 19.16 CURRENT|EA//14/14/0/0/5/500kHz//@EA_IB

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 25.0 (nA))

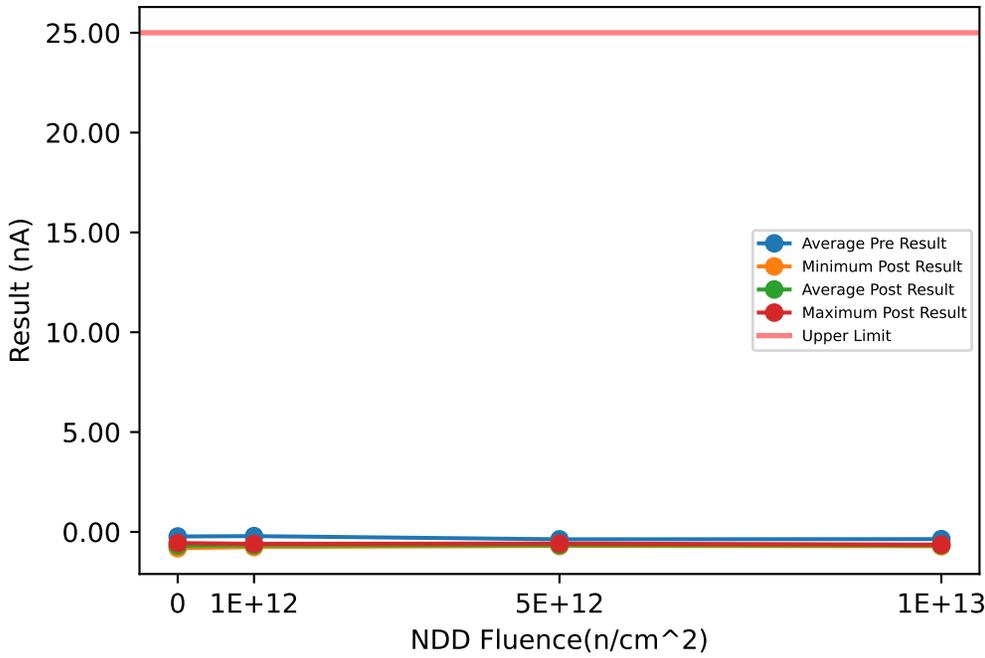| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.2028	-0.6467	-0.8495
2	1e+12	NDD	-0.203	-0.596	-0.393
3	1e+12	NDD	-0.2653	-0.7553	-0.49
4	1e+12	NDD	-0.576	-0.6678	-0.0918
5	5e+12	NDD	-0.1716	-0.706	-0.5344
6	5e+12	NDD	-0.1468	-0.6709	-0.5241
7	5e+12	NDD	-0.6523	-0.6866	-0.0343
8	5e+12	NDD	-0.5106	-0.5835	-0.0729
9	1e+13	NDD	-0.0811	-0.6373	-0.5562
10	1e+13	NDD	-0.1592	-0.6833	-0.5241
11	1e+13	NDD	-0.6992	-0.7178	-0.0186
12	1e+13	NDD	-0.5044	-0.6553	-0.1509
91	0	CORRELATION	0.0843	-0.5592	-0.6435
92	0	CORRELATION	-0.0999	-0.7052	-0.6053
93	0	CORRELATION	-0.3995	-0.8177	-0.4182
94	0	CORRELATION	-0.4982	-0.674	-0.1758

Test Statistics (nA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.4982	-0.22833	0.0843	0.26855	-0.8177	-0.68902	-0.5592	0.1063	-0.6435	-0.4607	-0.1758	0.21393
1e+12	-0.576	-0.21037	0.2028	0.32014	-0.7553	-0.66645	-0.596	0.066457	-0.8495	-0.45608	-0.0918	0.31231
5e+12	-0.6523	-0.37033	-0.1468	0.25076	-0.706	-0.66175	-0.5835	0.054106	-0.5344	-0.29142	-0.0343	0.2751
1e+13	-0.6992	-0.36097	-0.0811	0.29098	-0.7178	-0.67342	-0.6373	0.03512	-0.5562	-0.31245	-0.0186	0.26874

Device Test: 19.17 CURRENT|EA//12/12/0/0/5/100kHz//@EA_IB

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 25.0 (nA))

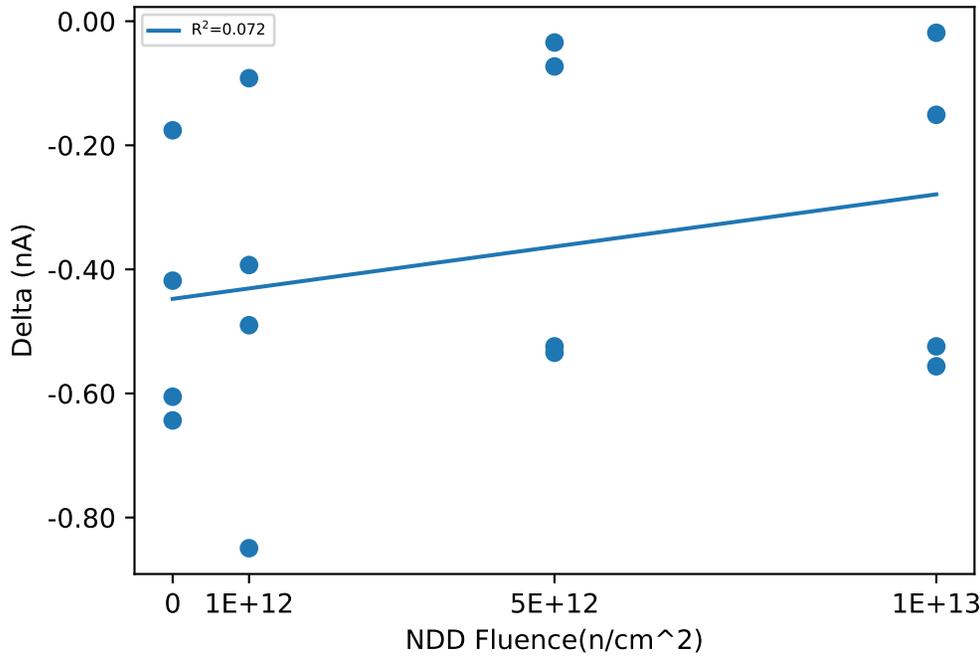| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.2933	-0.6498	-0.9431
2	1e+12	NDD	-0.0874	-0.6084	-0.521
3	1e+12	NDD	-0.0218	-0.5836	-0.5618
4	1e+12	NDD	-0.4515	-0.5461	-0.0946
5	5e+12	NDD	0.0749	-0.6842	-0.7591
6	5e+12	NDD	0.0687	-0.5897	-0.6584
7	5e+12	NDD	-0.4713	-0.5274	-0.0561
8	5e+12	NDD	-0.4888	-0.596	-0.1072
9	1e+13	NDD	-0.0468	-0.5904	-0.5436
10	1e+13	NDD	-0.1155	-0.6303	-0.5148
11	1e+13	NDD	-0.6929	-0.5149	0.178
12	1e+13	NDD	-0.4826	-0.5274	-0.0448
91	0	CORRELATION	-0.0905	-0.5186	-0.4281
92	0	CORRELATION	-0.1499	-0.5585	-0.4086
93	0	CORRELATION	-0.6211	-0.6866	-0.0655
94	0	CORRELATION	-0.5262	-0.571	-0.0448

Test Statistics (nA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.6211	-0.34692	-0.0905	0.26576	-0.6866	-0.58367	-0.5186	0.072164	-0.4281	-0.23675	-0.0448	0.21001
1e+12	-0.4515	-0.06685	0.2933	0.30557	-0.6498	-0.59698	-0.5461	0.043544	-0.9431	-0.53012	-0.0946	0.34704
5e+12	-0.4888	-0.20413	0.0749	0.3187	-0.6842	-0.59932	-0.5274	0.0645	-0.7591	-0.3952	-0.0561	0.36498
1e+13	-0.6929	-0.33445	-0.0468	0.30611	-0.6303	-0.56575	-0.5149	0.054255	-0.5436	-0.2313	0.178	0.356

Device Test: 19.18 CURRENT|EA//14/14/0/0/5/100kHz//@EA_IB

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta
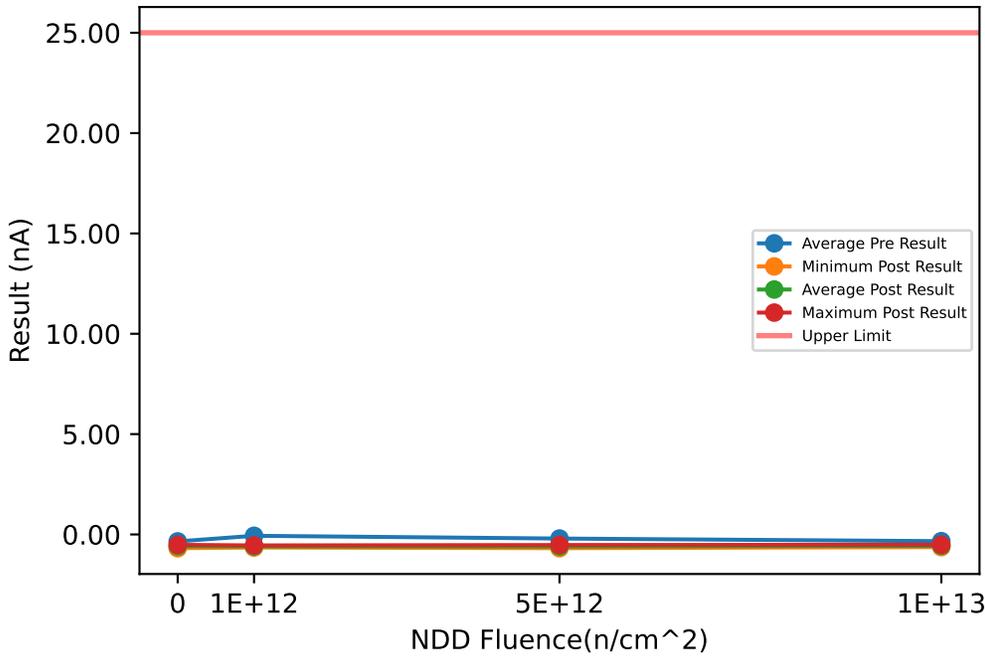

Test Results (Upper Limit = 25.0 (nA))

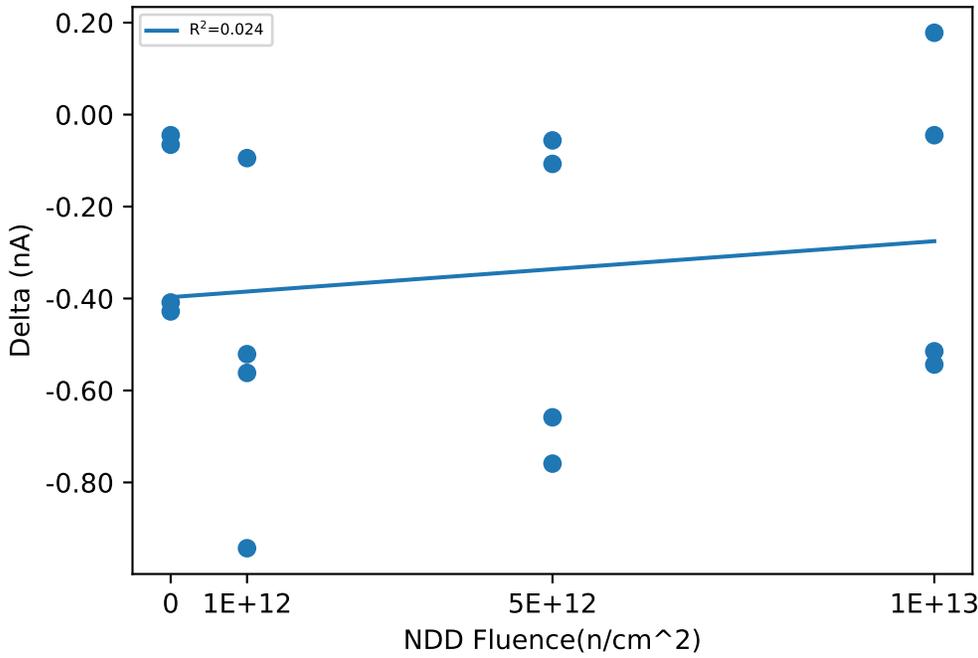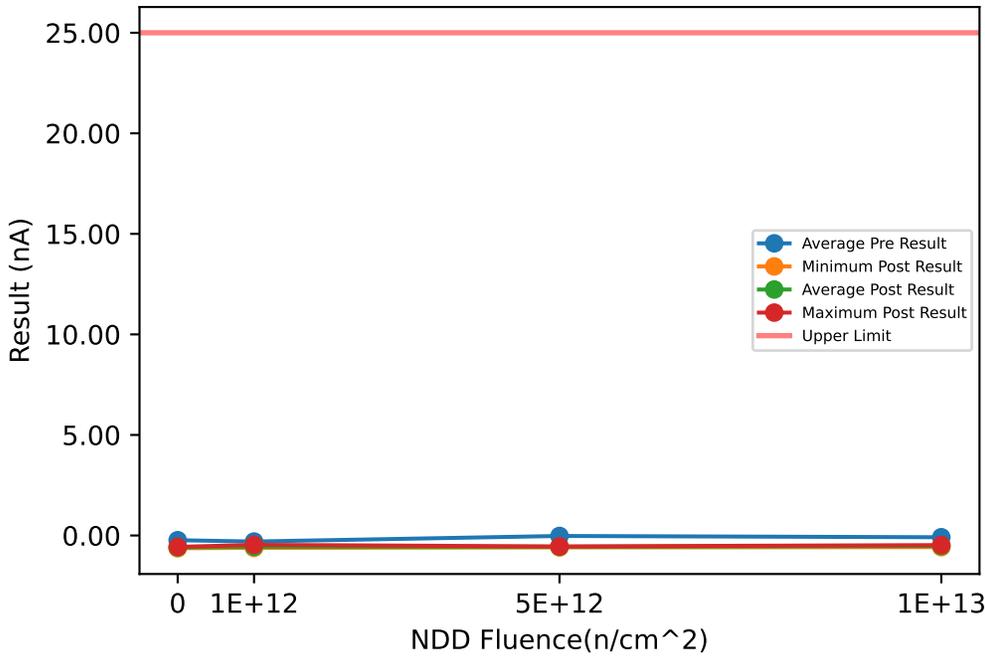| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	-0.0468	-0.4655	-0.4187
2	1e+12	NDD	-0.1124	-0.571	-0.4586
3	1e+12	NDD	-0.5088	-0.5836	-0.0748
4	1e+12	NDD	-0.5355	-0.6147	-0.0792
5	5e+12	NDD	0.3152	-0.553	-0.8682
6	5e+12	NDD	0.025	-0.5928	-0.6178
7	5e+12	NDD	-0.0593	-0.543	-0.4837
8	5e+12	NDD	-0.3736	-0.5586	-0.185
9	1e+13	NDD	0.2184	-0.5248	-0.7432
10	1e+13	NDD	-0.025	-0.4774	-0.4524
11	1e+13	NDD	-0.1436	-0.5774	-0.4338
12	1e+13	NDD	-0.3985	-0.5211	-0.1226
91	0	CORRELATION	0.0343	-0.5655	-0.5998
92	0	CORRELATION	-0.103	-0.6334	-0.5304
93	0	CORRELATION	-0.3933	-0.5899	-0.1966
94	0	CORRELATION	-0.4764	-0.5898	-0.1134

Test Statistics (nA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.4764	-0.2346	0.0343	0.24033	-0.6334	-0.59465	-0.5655	0.028269	-0.5998	-0.36005	-0.1134	0.24087
1e+12	-0.5355	-0.30088	-0.0468	0.25714	-0.6147	-0.5587	-0.4655	0.064791	-0.4586	-0.25782	-0.0748	0.20944
5e+12	-0.3736	-0.023175	0.3152	0.28338	-0.5928	-0.56185	-0.543	0.021619	-0.8682	-0.53868	-0.185	0.28458
1e+13	-0.3985	-0.087175	0.2184	0.25648	-0.5774	-0.52518	-0.4774	0.040933	-0.7432	-0.438	-0.1226	0.25354
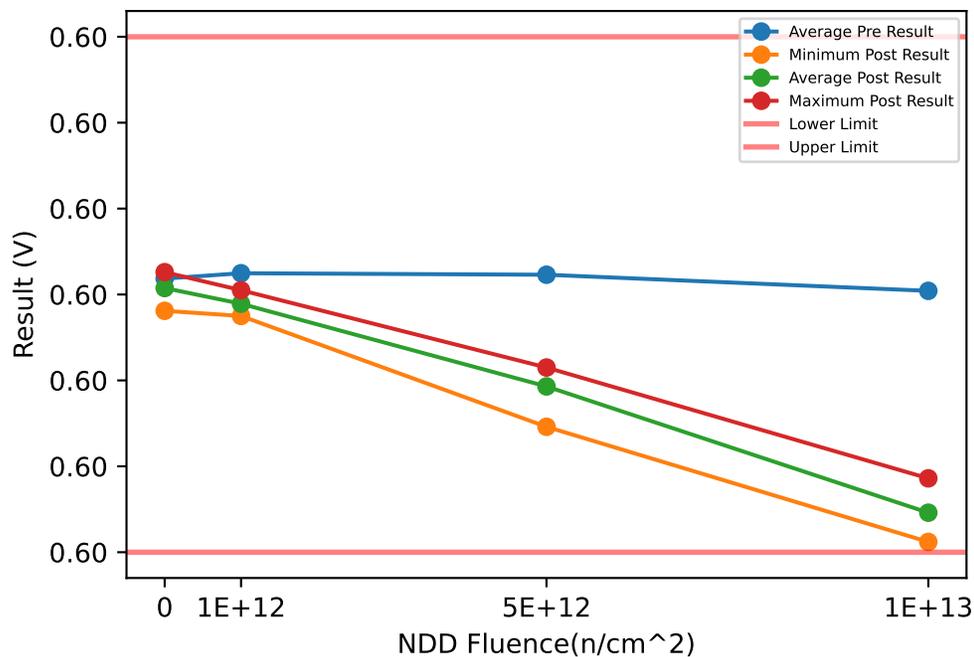
Device Test: 19.19 VOLTAGE|VREF//12/12/0/0/5/100kHz//@VREF_25C

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

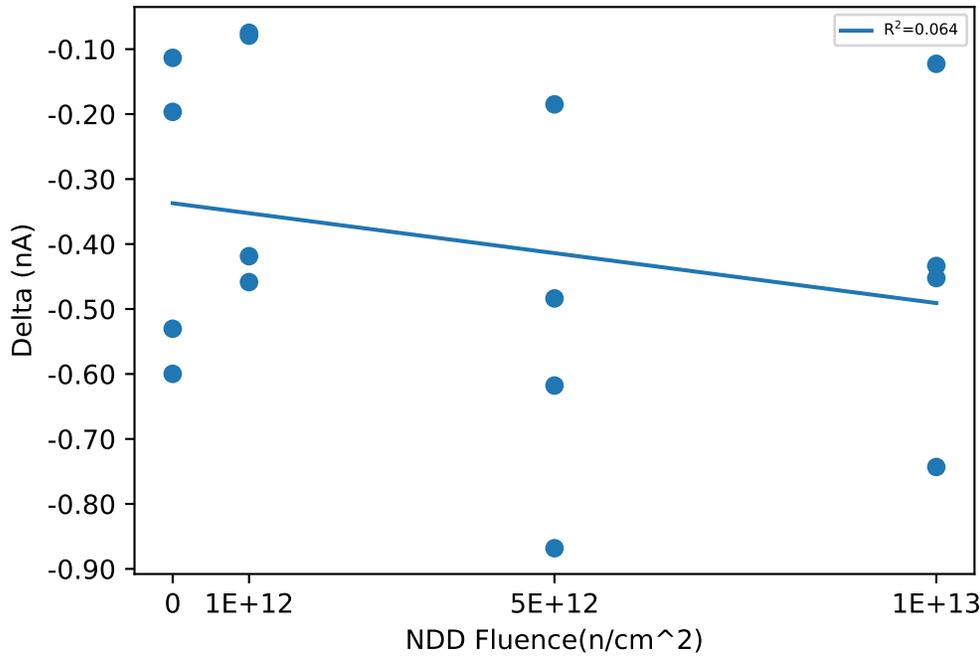| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.6004	0.60005	-0.00035
2	1e+12	NDD	0.60035	0.59996	-0.00039
3	1e+12	NDD	0.60017	0.59981	-0.00036
4	1e+12	NDD	0.60007	0.59975	-0.00032
5	5e+12	NDD	0.60036	0.59901	-0.00135
6	5e+12	NDD	0.59985	0.59846	-0.00139
7	5e+12	NDD	0.60032	0.59915	-0.00117
8	5e+12	NDD	0.60039	0.5991	-0.00129
9	1e+13	NDD	0.60043	0.59786	-0.00257
10	1e+13	NDD	0.59995	0.59712	-0.00283
11	1e+13	NDD	0.6	0.59752	-0.00248
12	1e+13	NDD	0.59979	0.59734	-0.00245
91	0	CORRELATION	0.60039	0.60026	-0.00013
92	0	CORRELATION	0.60028	0.60017	-0.00011
93	0	CORRELATION	0.59992	0.59981	-0.00011
94	0	CORRELATION	0.60015	0.60006	-9e-05
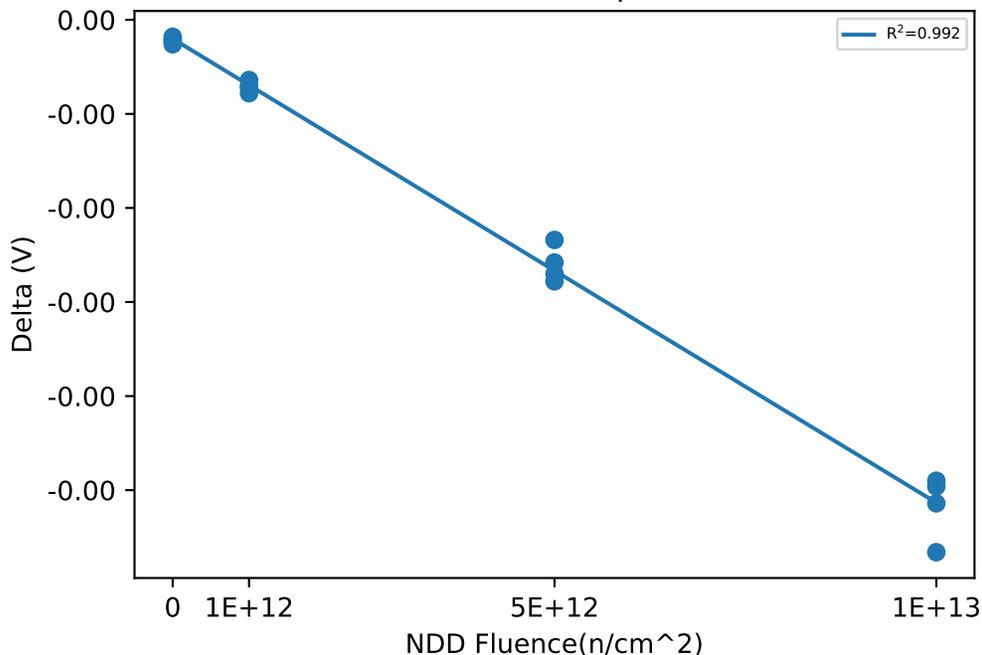
Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.59992	0.60018	0.60039	0.00020207	0.59981	0.60008	0.60026	0.00019468	-0.00013	-0.00011	-9e-05	1.633e-05
1e+12	0.60007	0.60025	0.6004	0.00015414	0.59975	0.59989	0.60005	0.0001372	-0.00039	-0.000355	-0.00032	2.8868e-05
5e+12	0.59985	0.60023	0.60039	0.00025495	0.59846	0.59893	0.59915	0.00031864	-0.00139	-0.0013	-0.00117	9.5917e-05
1e+13	0.59979	0.60004	0.60043	0.00027342	0.59712	0.59746	0.59786	0.00031284	-0.00283	-0.0025825	-0.00245	0.0001727
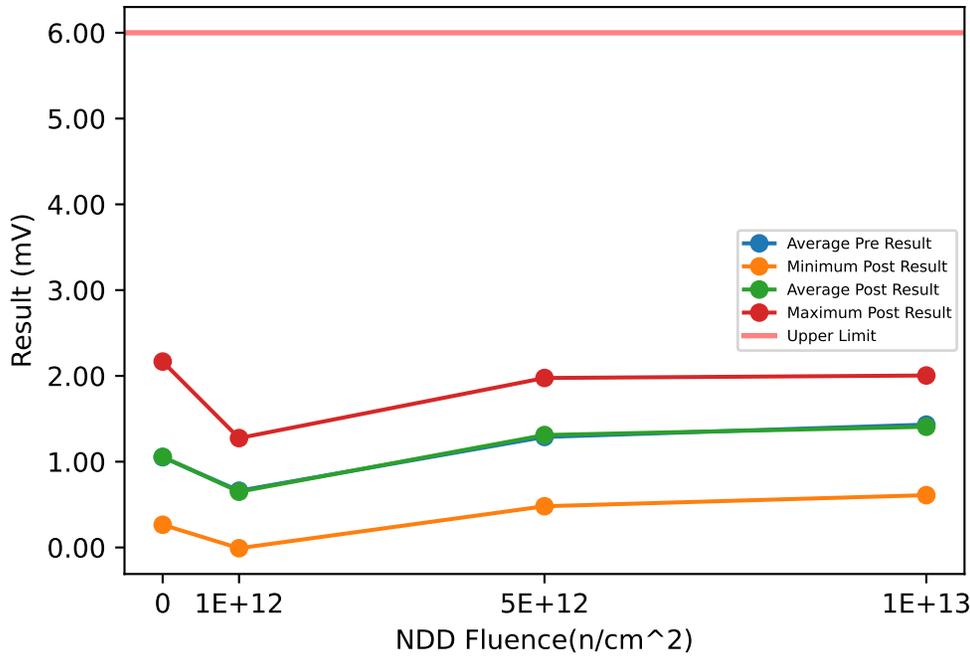
Device Test: 19.21 VOLTAGE|OFFSET//12/12/0/0/5/100kHz//@EA_OS

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 6.0 (mV))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.7529	0.7373	-0.0156
2	1e+12	NDD	0.6251	0.5944	-0.0307
3	1e+12	NDD	1.2791	1.2747	-0.0044
4	1e+12	NDD	-0.0117	-0.0088	0.0029
5	5e+12	NDD	1.6014	1.5872	-0.0142
6	5e+12	NDD	0.4419	0.4805	0.0386
7	5e+12	NDD	1.9424	1.9759	0.0335
8	5e+12	NDD	1.1671	1.1988	0.0317
9	1e+13	NDD	1.6576	1.6089	-0.0487
10	1e+13	NDD	0.6357	0.6098	-0.0259
11	1e+13	NDD	2.0336	2.0047	-0.0289
12	1e+13	NDD	1.4026	1.4038	0.0012
91	0	CORRELATION	2.164	2.167	0.003
92	0	CORRELATION	0.6276	0.6304	0.0028
93	0	CORRELATION	0.2641	0.2647	0.0006
94	0	CORRELATION	1.1529	1.1648	0.0119
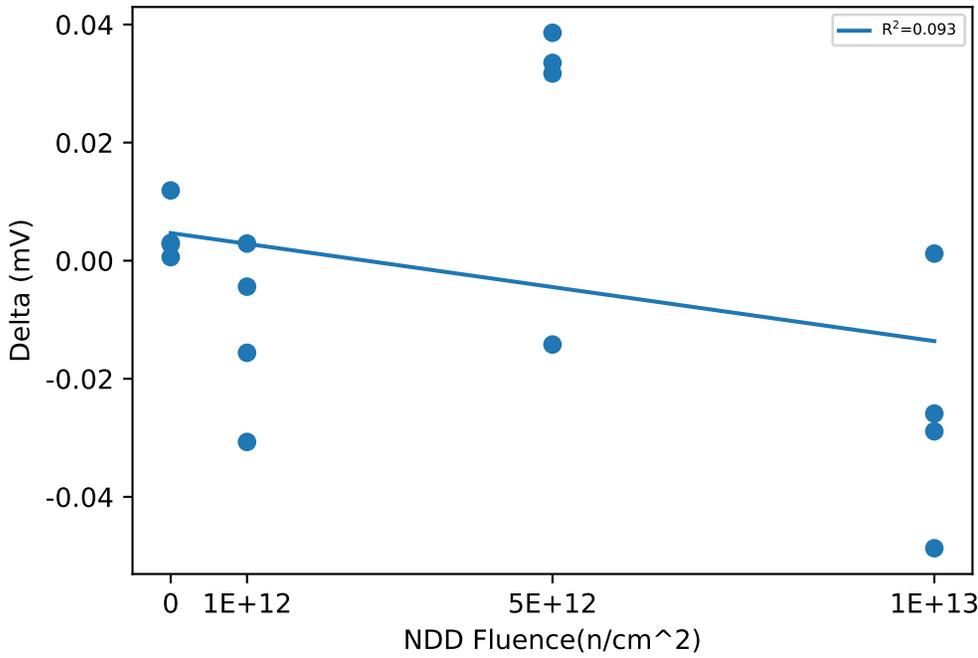
Test Statistics (mV)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.2641	1.0522	2.164	0.82616	0.2647	1.0567	2.167	0.82733	0.0006	0.004575	0.0119	0.0050029
1e+12	-0.0117	0.66135	1.2791	0.53051	-0.0088	0.6494	1.2747	0.52757	-0.0307	-0.01195	0.0029	0.014633
5e+12	0.4419	1.2882	1.9424	0.64729	0.4805	1.3106	1.9759	0.63789	-0.0142	0.0224	0.0386	0.024574
1e+13	0.6357	1.4324	2.0336	0.59098	0.6098	1.4068	2.0047	0.58695	-0.0487	-0.025575	0.0012	0.020517
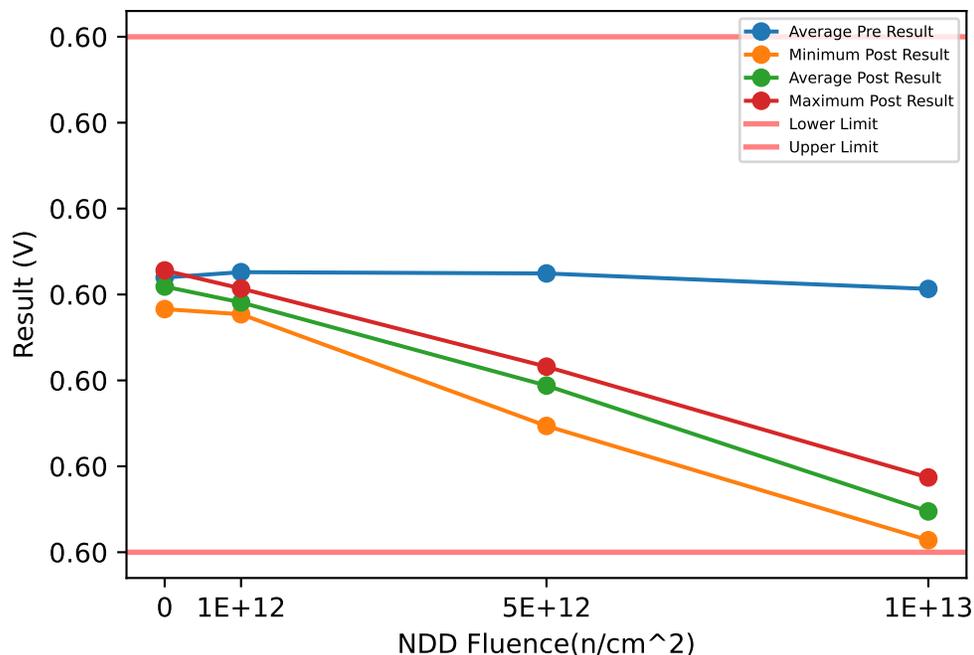
Device Test: 19.22 VOLTAGE|VREF//14/14/0/0/5/100kHz//@VREF_25C

## NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.60042	0.60007	-0.00035
2	1e+12	NDD	0.60036	0.59997	-0.00039
3	1e+12	NDD	0.60018	0.59982	-0.00036
4	1e+12	NDD	0.60008	0.59977	-0.00031
5	5e+12	NDD	0.60037	0.59902	-0.00135
6	5e+12	NDD	0.59987	0.59847	-0.0014
7	5e+12	NDD	0.60033	0.59916	-0.00117
8	5e+12	NDD	0.60041	0.59911	-0.0013
9	1e+13	NDD	0.60045	0.59787	-0.00258
10	1e+13	NDD	0.59998	0.59714	-0.00284
11	1e+13	NDD	0.60002	0.59753	-0.00249
12	1e+13	NDD	0.59981	0.59736	-0.00245
91	0	CORRELATION	0.6004	0.60028	-0.00012
92	0	CORRELATION	0.60029	0.60019	-0.0001
93	0	CORRELATION	0.59993	0.59983	-0.0001
94	0	CORRELATION	0.60017	0.60007	-0.0001
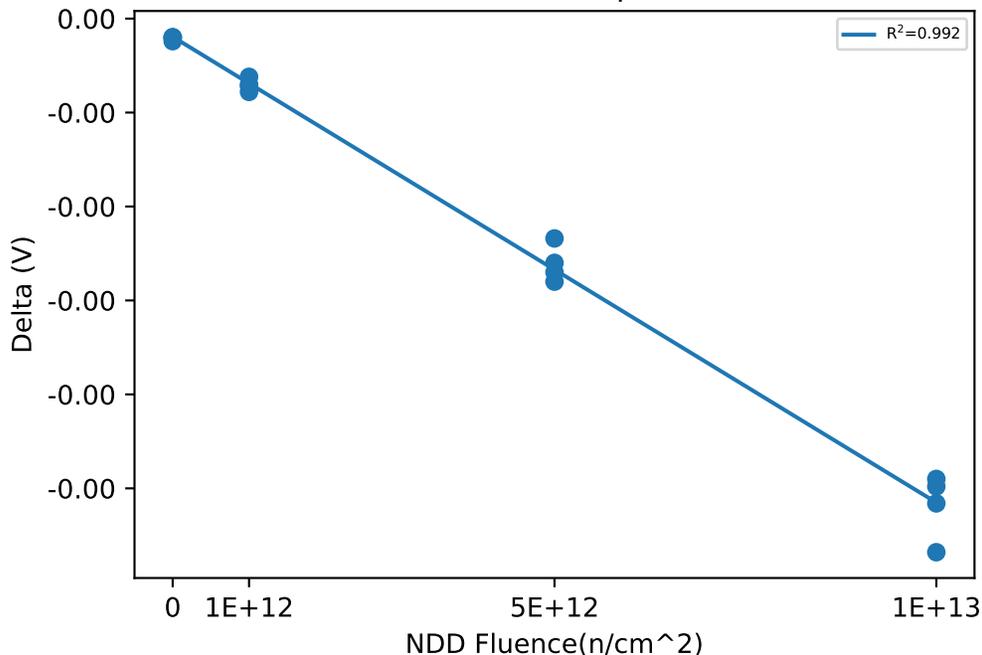
Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.59993	0.6002	0.6004	0.00020156	0.59983	0.60009	0.60028	0.000195	-0.00012	-0.000105	-0.0001	1e-05
1e+12	0.60008	0.60026	0.60042	0.00015748	0.59977	0.59991	0.60007	0.00013769	-0.00039	-0.0003525	-0.00031	3.304e-05
5e+12	0.59987	0.60025	0.60041	0.00025212	0.59847	0.59894	0.59916	0.00031864	-0.0014	-0.001305	-0.00117	9.8826e-05
1e+13	0.59981	0.60006	0.60045	0.00027234	0.59714	0.59747	0.59787	0.00030795	-0.00284	-0.00259	-0.00245	0.00017531
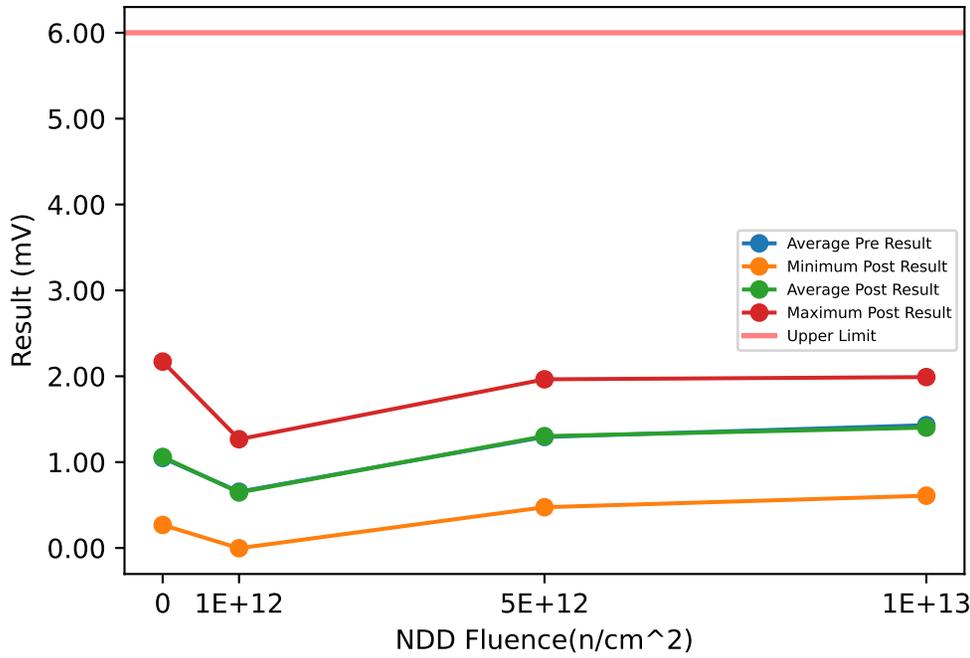
Device Test: 19.24 VOLTAGE|OFFSET//14/14/0/0/5/100kHz//@EA_OS

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 6.0 (mV))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.7545	0.7312	-0.0233
2	1e+12	NDD	0.6125	0.5906	-0.0219
3	1e+12	NDD	1.274	1.2665	-0.0075
4	1e+12	NDD	-0.0195	-0.0026	0.0169
5	5e+12	NDD	1.6003	1.576	-0.0243
6	5e+12	NDD	0.4435	0.4749	0.0314
7	5e+12	NDD	1.9525	1.9645	0.012
8	5e+12	NDD	1.1774	1.1945	0.0171
9	1e+13	NDD	1.6548	1.6002	-0.0546
10	1e+13	NDD	0.6469	0.6092	-0.0377
11	1e+13	NDD	2.021	1.9904	-0.0306
12	1e+13	NDD	1.3987	1.4073	0.0086
91	0	CORRELATION	2.1547	2.1705	0.0158
92	0	CORRELATION	0.6247	0.6321	0.0074
93	0	CORRELATION	0.2656	0.2685	0.0029
94	0	CORRELATION	1.1483	1.1706	0.0223
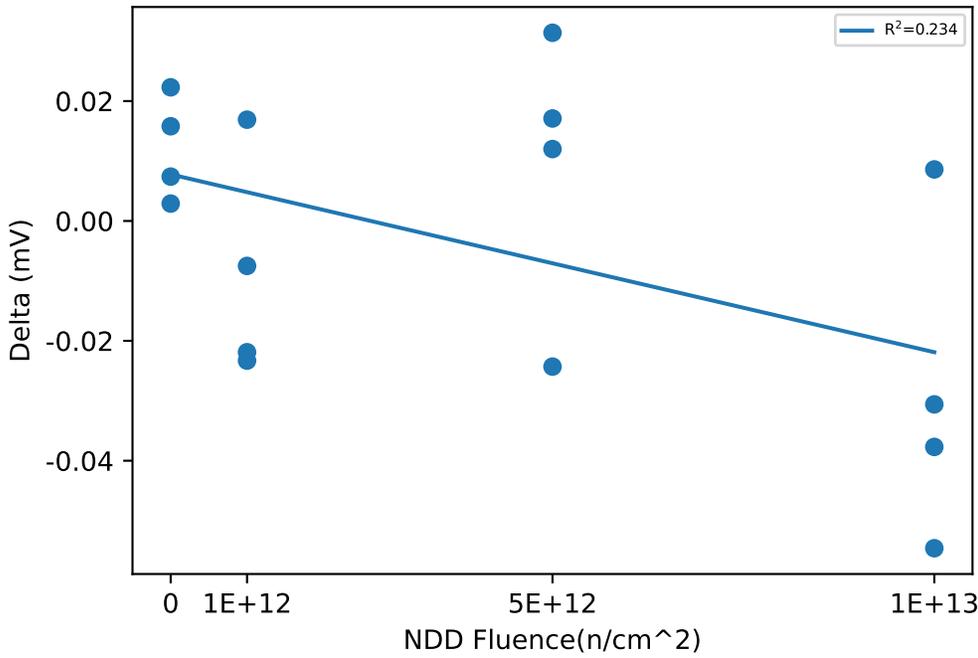
Test Statistics (mV)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.2656	1.0483	2.1547	0.82182	0.2685	1.0604	2.1705	0.82765	0.0029	0.0121	0.0223	0.0086499
1e+12	-0.0195	0.65538	1.274	0.53223	-0.0026	0.64642	1.2665	0.52155	-0.0233	-0.00895	0.0169	0.018654
5e+12	0.4435	1.2934	1.9525	0.6492	0.4749	1.3025	1.9645	0.63499	-0.0243	0.00905	0.0314	0.023701
1e+13	0.6469	1.4304	2.021	0.58139	0.6092	1.4018	1.9904	0.58139	-0.0546	-0.028575	0.0086	0.02675
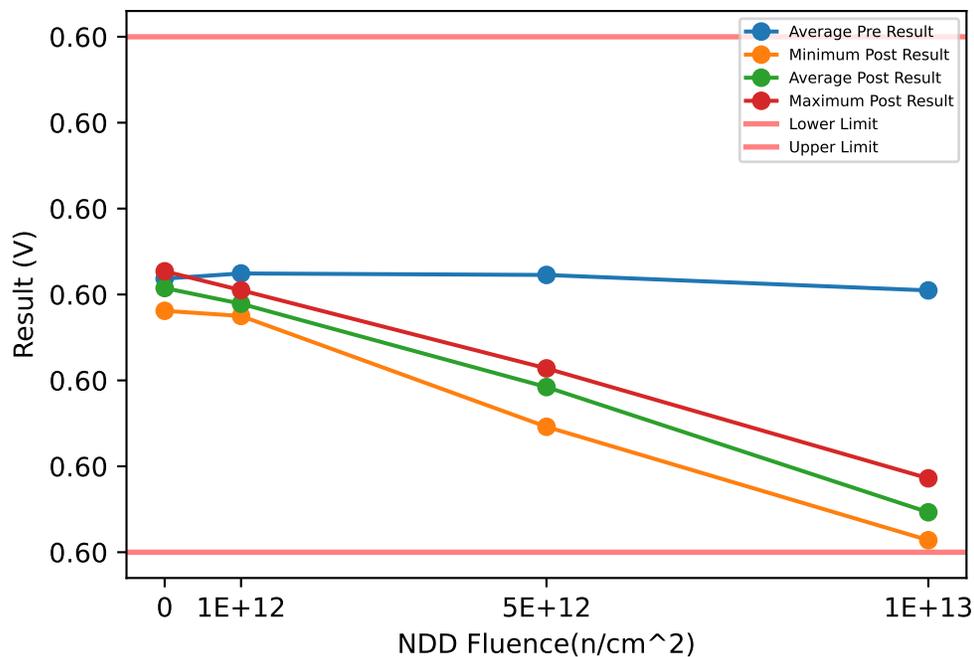
Device Test: 19.25 VOLTAGE|VREF//12/12/0/0/5/500kHz//@VREF_25C

## NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.6004	0.60005	-0.00035
2	1e+12	NDD	0.60035	0.59996	-0.00039
3	1e+12	NDD	0.60016	0.59981	-0.00035
4	1e+12	NDD	0.60007	0.59975	-0.00032
5	5e+12	NDD	0.60036	0.599	-0.00136
6	5e+12	NDD	0.59985	0.59846	-0.00139
7	5e+12	NDD	0.6003	0.59914	-0.00116
8	5e+12	NDD	0.6004	0.59909	-0.00131
9	1e+13	NDD	0.60043	0.59786	-0.00257
10	1e+13	NDD	0.59997	0.59714	-0.00283
11	1e+13	NDD	0.6	0.59752	-0.00248
12	1e+13	NDD	0.59979	0.59734	-0.00245
91	0	CORRELATION	0.60039	0.60027	-0.00012
92	0	CORRELATION	0.60028	0.60017	-0.00011
93	0	CORRELATION	0.59991	0.59981	-0.0001
94	0	CORRELATION	0.60016	0.60005	-0.00011
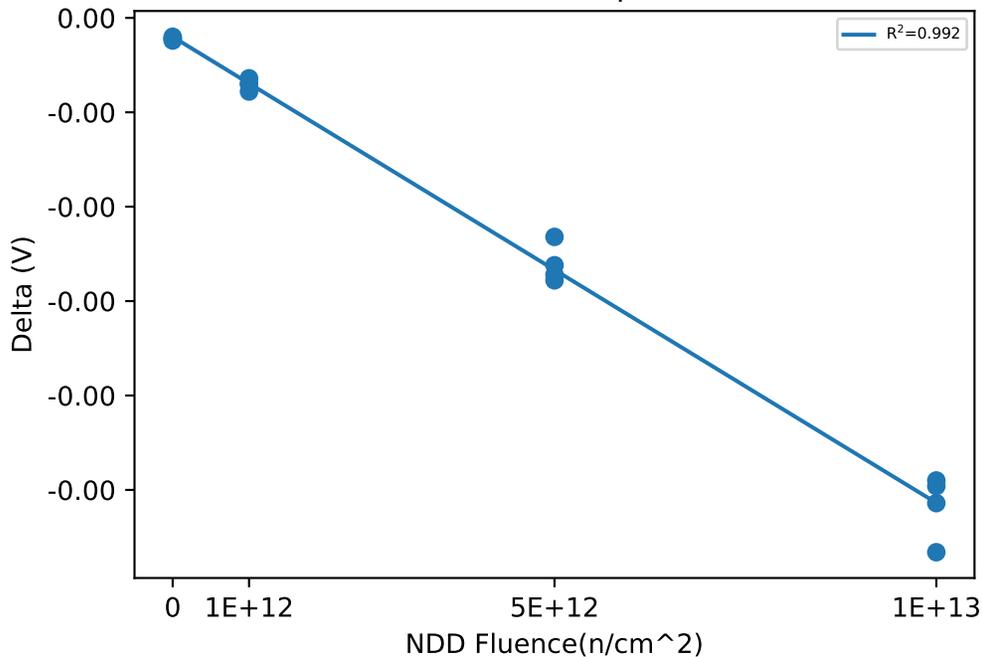
Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.59991	0.60018	0.60039	0.00020599	0.59981	0.60007	0.60027	0.00019824	-0.00012	-0.00011	-0.0001	8.165e-06
1e+12	0.60007	0.60025	0.6004	0.00015588	0.59975	0.59989	0.60005	0.0001372	-0.00039	-0.0003525	-0.00032	2.8723e-05
5e+12	0.59985	0.60023	0.6004	0.000255	0.59846	0.59892	0.59914	0.00031373	-0.00139	-0.001305	-0.00116	0.00010214
1e+13	0.59979	0.60005	0.60043	0.00027134	0.59714	0.59747	0.59786	0.00030567	-0.00283	-0.0025825	-0.00245	0.0001727
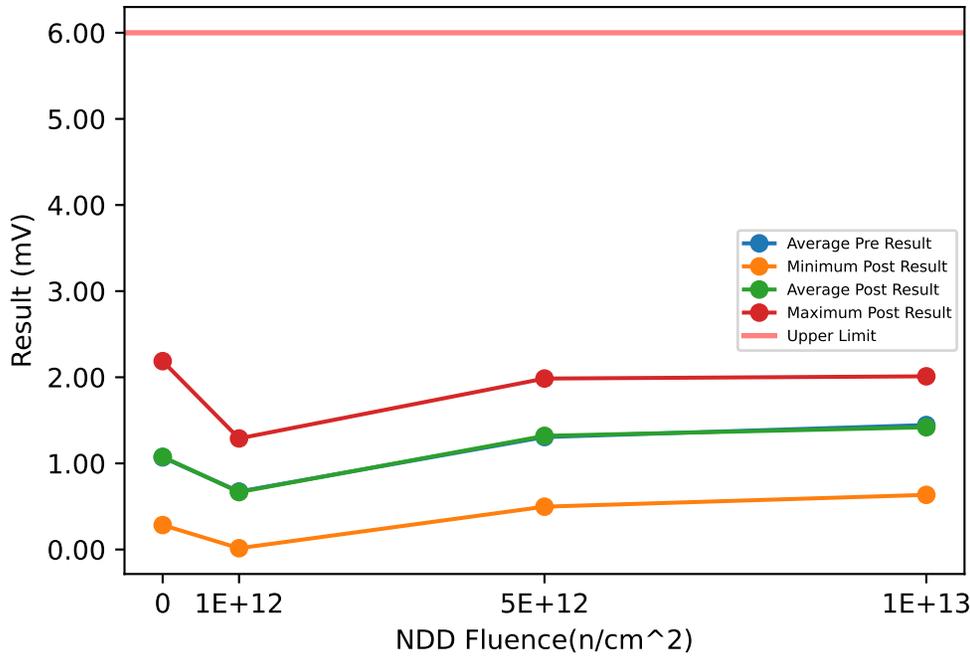
Device Test: 19.27 VOLTAGE|OFFSET//12/12/0/0/5/500kHz//@EA_OS

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 6.0 (mV))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.7674	0.7531	-0.0143
2	1e+12	NDD	0.6353	0.6075	-0.0278
3	1e+12	NDD	1.2869	1.2894	0.0025
4	1e+12	NDD	0.0018	0.0149	0.0131
5	5e+12	NDD	1.6172	1.5918	-0.0254
6	5e+12	NDD	0.45	0.4972	0.0472
7	5e+12	NDD	1.9601	1.9851	0.025
8	5e+12	NDD	1.1952	1.2046	0.0094
9	1e+13	NDD	1.6662	1.6192	-0.047
10	1e+13	NDD	0.6623	0.6345	-0.0278
11	1e+13	NDD	2.0405	2.011	-0.0295
12	1e+13	NDD	1.4121	1.4132	0.0011
91	0	CORRELATION	2.1813	2.1871	0.0058
92	0	CORRELATION	0.6437	0.653	0.0093
93	0	CORRELATION	0.2773	0.2839	0.0066
94	0	CORRELATION	1.1771	1.1824	0.0053
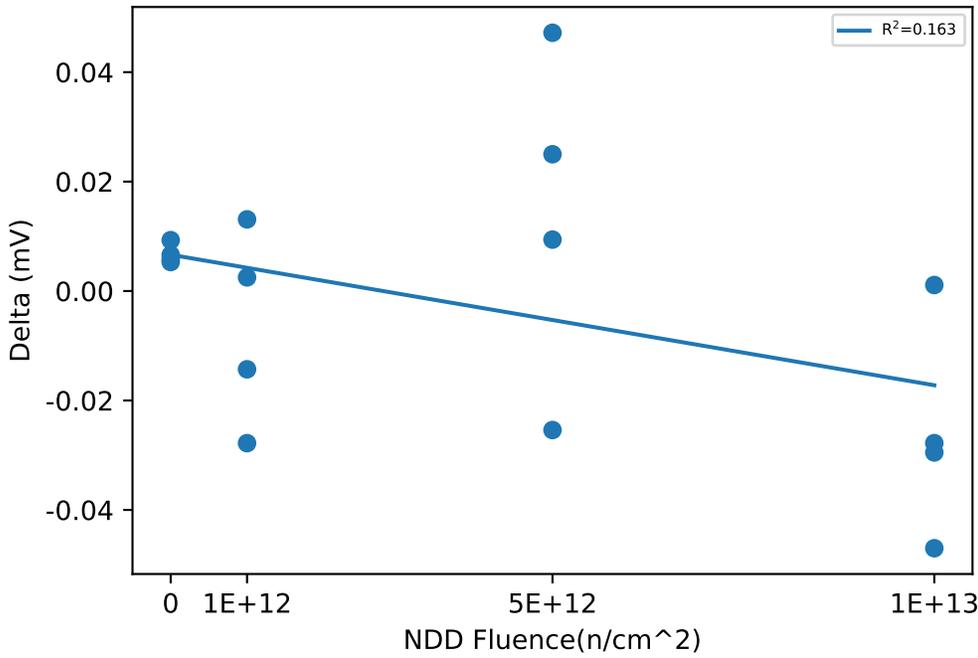
Test Statistics (mV)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.2773	1.0698	2.1813	0.82796	0.2839	1.0766	2.1871	0.82709	0.0053	0.00675	0.0093	0.0017823
1e+12	0.0018	0.67285	1.2869	0.52843	0.0149	0.66623	1.2894	0.52395	-0.0278	-0.006625	0.0131	0.01807
5e+12	0.45	1.3056	1.9601	0.65056	0.4972	1.3197	1.9851	0.63418	-0.0254	0.01405	0.0472	0.030533
1e+13	0.6623	1.4453	2.0405	0.58231	0.6345	1.4195	2.011	0.57908	-0.047	-0.0258	0.0011	0.019923
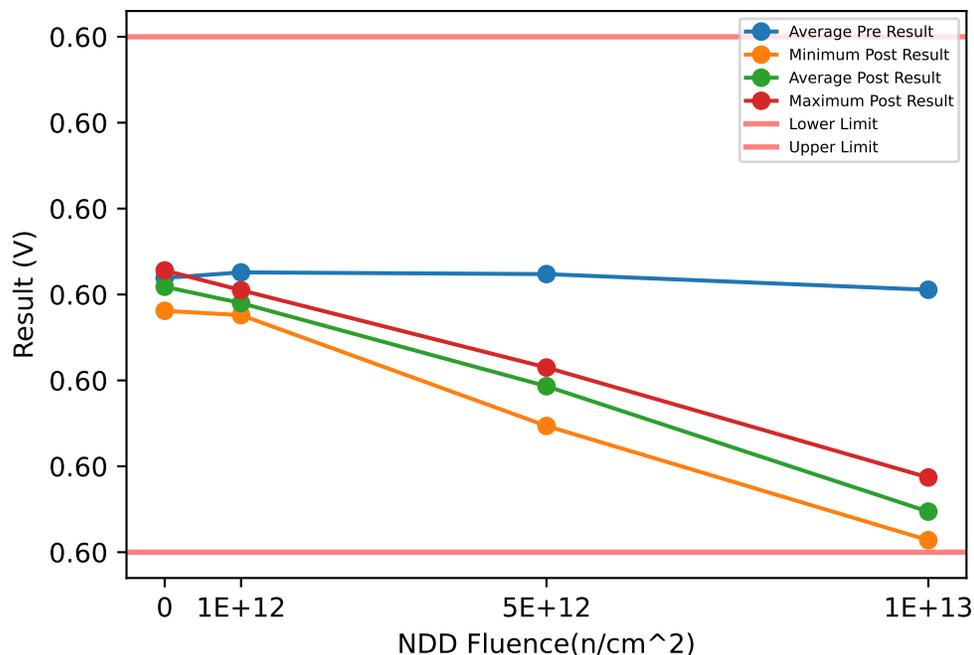
Device Test: 19.28 VOLTAGE|VREF//14/14/0/0/5/500kHz//@VREF_25C

NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.60041	0.60005	-0.00036
2	1e+12	NDD	0.60037	0.59997	-0.0004
3	1e+12	NDD	0.60017	0.59982	-0.00035
4	1e+12	NDD	0.60008	0.59976	-0.00032
5	5e+12	NDD	0.60037	0.59901	-0.00136
6	5e+12	NDD	0.59985	0.59847	-0.00138
7	5e+12	NDD	0.60033	0.59915	-0.00118
8	5e+12	NDD	0.6004	0.5991	-0.0013
9	1e+13	NDD	0.60044	0.59787	-0.00257
10	1e+13	NDD	0.59997	0.59714	-0.00283
11	1e+13	NDD	0.6	0.59752	-0.00248
12	1e+13	NDD	0.59981	0.59736	-0.00245
91	0	CORRELATION	0.6004	0.60028	-0.00012
92	0	CORRELATION	0.60029	0.6002	-9e-05
93	0	CORRELATION	0.59992	0.59981	-0.00011
94	0	CORRELATION	0.60016	0.60007	-9e-05
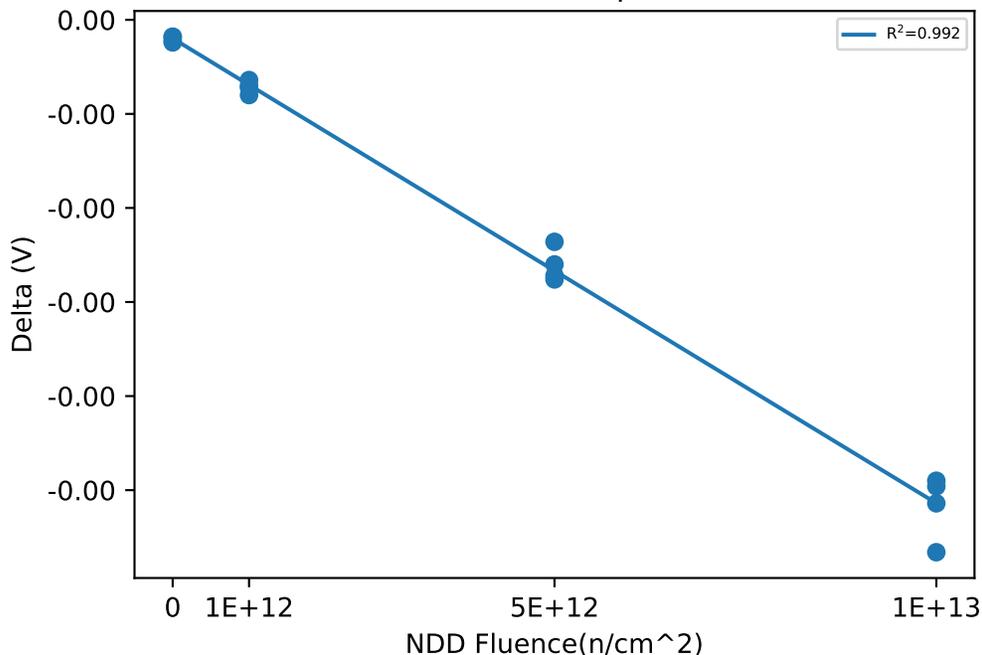
Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.59992	0.60019	0.6004	0.00020646	0.59981	0.60009	0.60028	0.00020575	-0.00012	-0.0001025	-9e-05	1.5e-05
1e+12	0.60008	0.60026	0.60041	0.00015819	0.59976	0.5999	0.60005	0.00013342	-0.0004	-0.0003575	-0.00032	3.304e-05
5e+12	0.59985	0.60024	0.6004	0.00025992	0.59847	0.59893	0.59915	0.00031373	-0.00138	-0.001305	-0.00118	9e-05
1e+13	0.59981	0.60006	0.60044	0.00026988	0.59714	0.59747	0.59787	0.00030739	-0.00283	-0.0025825	-0.00245	0.0001727
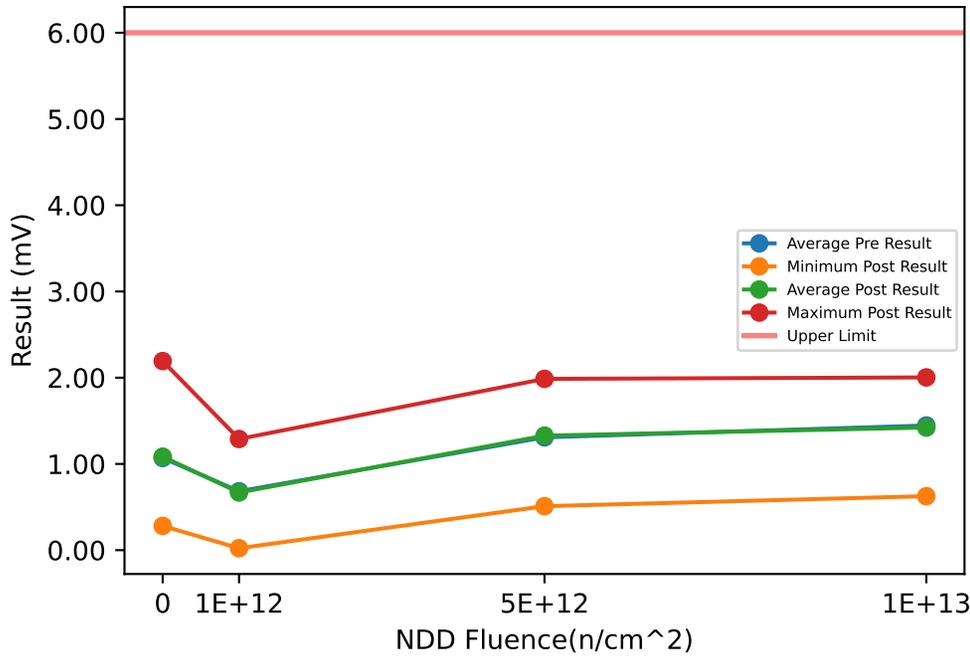
Device Test: 19.30 VOLTAGE|OFFSET//14/14/0/0/5/500kHz//@EA_OS

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 6.0 (mV))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.7757	0.7519	-0.0238
2	1e+12	NDD	0.6455	0.6112	-0.0343
3	1e+12	NDD	1.2995	1.2891	-0.0104
4	1e+12	NDD	0.0108	0.0225	0.0117
5	5e+12	NDD	1.6192	1.6	-0.0192
6	5e+12	NDD	0.4559	0.51	0.0541
7	5e+12	NDD	1.969	1.9865	0.0175
8	5e+12	NDD	1.1895	1.2151	0.0256
9	1e+13	NDD	1.6711	1.6221	-0.049
10	1e+13	NDD	0.6592	0.6261	-0.0331
11	1e+13	NDD	2.0337	2.0034	-0.0303
12	1e+13	NDD	1.4179	1.4367	0.0188
91	0	CORRELATION	2.1736	2.1929	0.0193
92	0	CORRELATION	0.6511	0.6648	0.0137
93	0	CORRELATION	0.2764	0.2812	0.0048
94	0	CORRELATION	1.1753	1.1973	0.022
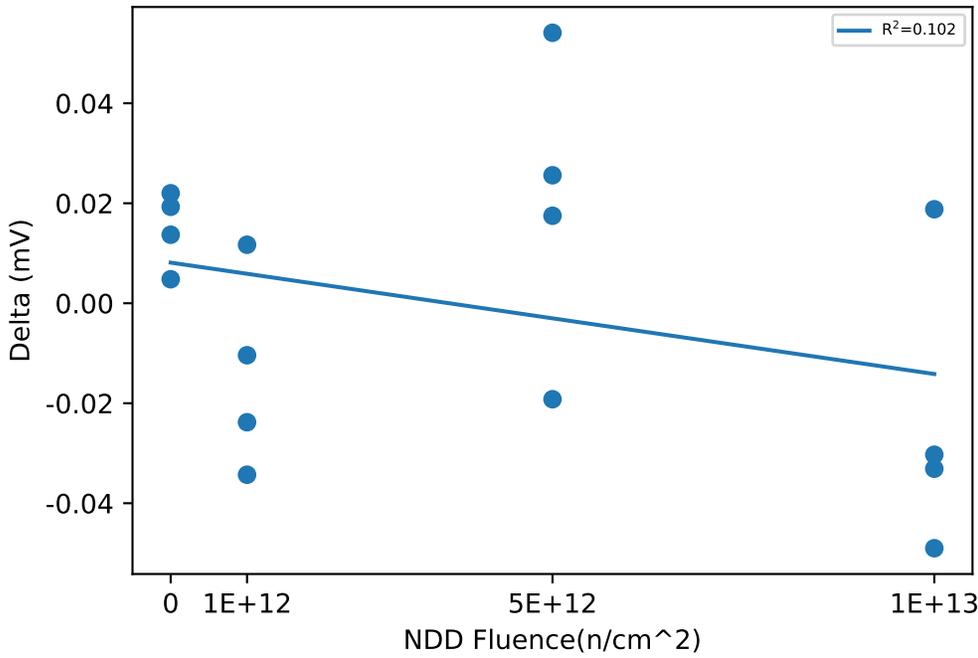
Test Statistics (mV)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.2764	1.0691	2.1736	0.82347	0.2812	1.084	2.1929	0.8292	0.0048	0.01495	0.022	0.0075985
1e+12	0.0108	0.68288	1.2995	0.52976	0.0225	0.66868	1.2891	0.52048	-0.0343	-0.0142	0.0117	0.019845
5e+12	0.4559	1.3084	1.969	0.65163	0.51	1.3279	1.9865	0.62968	-0.0192	0.0195	0.0541	0.0302
1e+13	0.6592	1.4455	2.0337	0.58192	0.6261	1.4221	2.0034	0.58073	-0.049	-0.0234	0.0188	0.029314

Device Test: 19.31 VOLTAGE|VREF//12/12/0/1000/5/100kHz//@VREF_25C

NDD vs Result Stats

Legend:
- Average Pre Result
- Minimum Post Result
- Average Post Result
- Maximum Post Result
- Lower Limit
- Upper Limit

NDD vs Post - Pre Exposure Delta

R²=0.991

Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.60042	0.60008	-0.00034
2	1e+12	NDD	0.60037	0.59998	-0.00039
3	1e+12	NDD	0.60018	0.59984	-0.00034
4	1e+12	NDD	0.60008	0.59977	-0.00031
5	5e+12	NDD	0.60039	0.59902	-0.00137
6	5e+12	NDD	0.59987	0.59848	-0.00139
7	5e+12	NDD	0.60034	0.59918	-0.00116
8	5e+12	NDD	0.60043	0.59912	-0.00131
9	1e+13	NDD	0.60046	0.59789	-0.00257
10	1e+13	NDD	0.59998	0.59715	-0.00283
11	1e+13	NDD	0.60002	0.59753	-0.00249
12	1e+13	NDD	0.59981	0.59737	-0.00244
91	0	CORRELATION	0.60041	0.60028	-0.00013
92	0	CORRELATION	0.60031	0.6002	-0.00011
93	0	CORRELATION	0.59995	0.59983	-0.00012
94	0	CORRELATION	0.60018	0.60009	-9e-05

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.59995	0.60021	0.60041	0.00019873	0.59983	0.6001	0.60028	0.00019613	-0.00013	-0.0001125	-9e-05	1.7078e-05
1e+12	0.60008	0.60026	0.60042	0.00015966	0.59977	0.59992	0.60008	0.00013913	-0.00039	-0.000345	-0.00031	3.3166e-05
5e+12	0.59987	0.60026	0.60043	0.00026094	0.59848	0.59895	0.59918	0.00032021	-0.00139	-0.0013075	-0.00116	0.00010404
1e+13	0.59981	0.60007	0.60046	0.00027705	0.59715	0.59749	0.59789	0.00031172	-0.00283	-0.0025825	-0.00244	0.00017347

Device Test: 19.33 VOLTAGE|VREF//14/14/0/1000/5/100kHz//@VREF_25C

NDD vs Result Stats

Legend:
- Average Pre Result
- Minimum Post Result
- Average Post Result
- Maximum Post Result
- Lower Limit
- Upper Limit

X-axis: NDD Fluence(n/cm^2)
Y-axis: Result (V)

NDD vs Post - Pre Exposure Delta

$R^2 = 0.992$

X-axis: NDD Fluence(n/cm^2)
Y-axis: Delta (V)

Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.60045	0.6001	-0.00035
2	1e+12	NDD	0.60039	0.6	-0.00039
3	1e+12	NDD	0.6002	0.59986	-0.00034
4	1e+12	NDD	0.60009	0.59979	-0.0003
5	5e+12	NDD	0.60039	0.59903	-0.00136
6	5e+12	NDD	0.59988	0.5985	-0.00138
7	5e+12	NDD	0.60037	0.5992	-0.00117
8	5e+12	NDD	0.60045	0.59914	-0.00131
9	1e+13	NDD	0.60049	0.59791	-0.00258
10	1e+13	NDD	0.6	0.59717	-0.00283
11	1e+13	NDD	0.60004	0.59757	-0.00247
12	1e+13	NDD	0.59984	0.59738	-0.00246
91	0	CORRELATION	0.60043	0.60031	-0.00012
92	0	CORRELATION	0.60032	0.60022	-0.0001
93	0	CORRELATION	0.59996	0.59986	-0.0001
94	0	CORRELATION	0.60019	0.6001	-9e-05
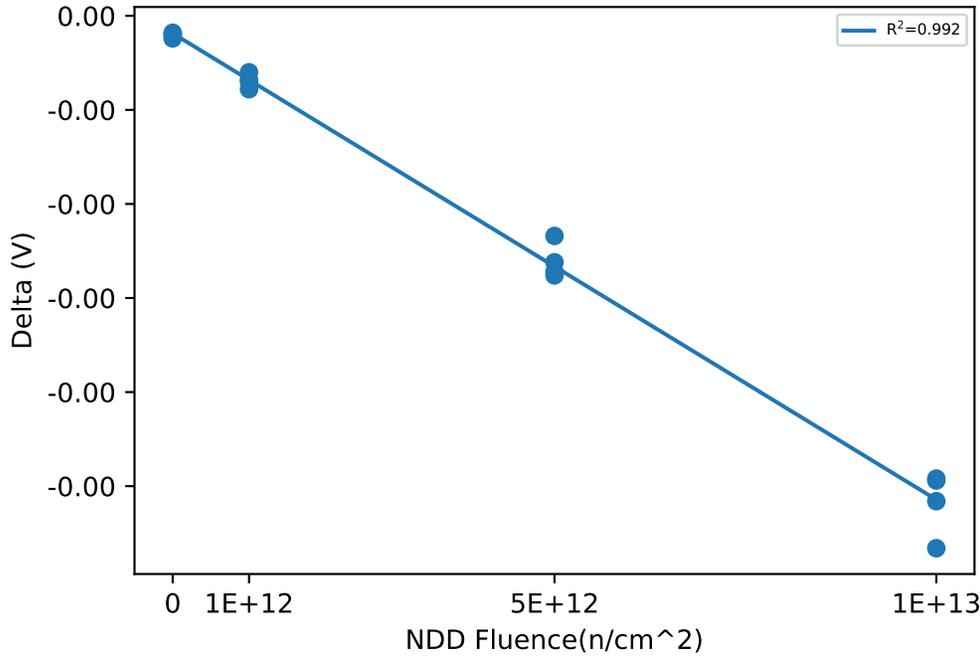
Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.59996	0.60023	0.60043	0.00020207	0.59986	0.60012	0.60031	0.000195	-0.00012	-0.0001025	-9e-05	1.2583e-05
1e+12	0.60009	0.60028	0.60045	0.00016681	0.59979	0.59994	0.6001	0.00013913	-0.00039	-0.000345	-0.0003	3.6968e-05
5e+12	0.59988	0.60027	0.60045	0.00026387	0.5985	0.59897	0.5992	0.00031952	-0.00138	-0.001305	-0.00117	9.4692e-05
1e+13	0.59984	0.60009	0.60049	0.00027873	0.59717	0.59751	0.59791	0.00031415	-0.00283	-0.002585	-0.00246	0.00017214
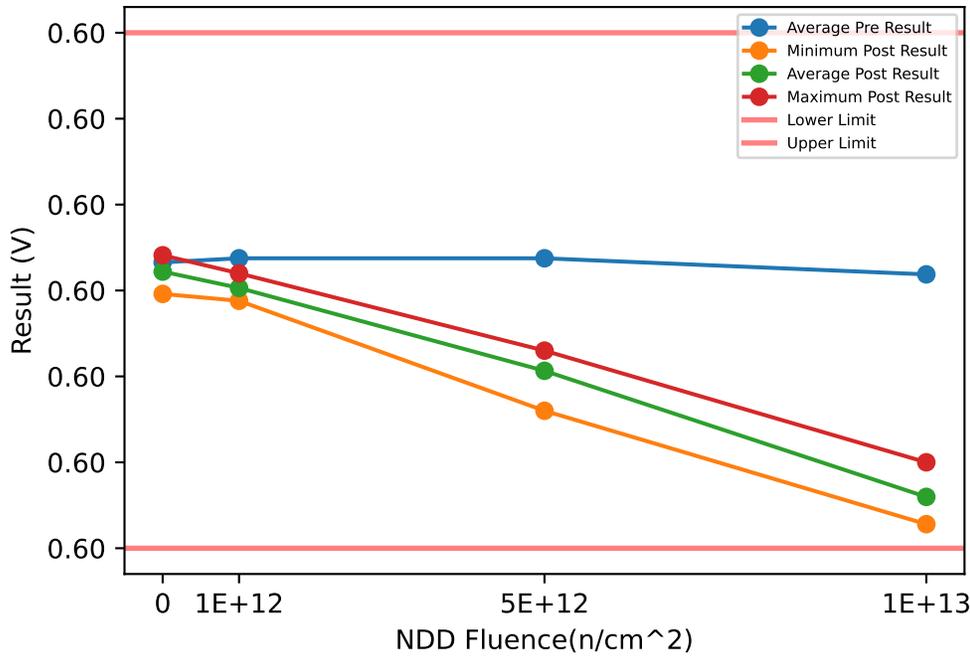
Device Test: 19.35 VOLTAGE|VREF//12/12/0/1000/5/500kHz//@VREF_25C

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta


Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.60054	0.6002	-0.00034
2	1e+12	NDD	0.60048	0.60009	-0.00039
3	1e+12	NDD	0.60029	0.59995	-0.00034
4	1e+12	NDD	0.60019	0.59988	-0.00031
5	5e+12	NDD	0.6005	0.59913	-0.00137
6	5e+12	NDD	0.59999	0.5986	-0.00139
7	5e+12	NDD	0.60047	0.5993	-0.00117
8	5e+12	NDD	0.60054	0.59923	-0.00131
9	1e+13	NDD	0.60058	0.598	-0.00258
10	1e+13	NDD	0.60011	0.59728	-0.00283
11	1e+13	NDD	0.60013	0.59764	-0.00249
12	1e+13	NDD	0.59993	0.59747	-0.00246
91	0	CORRELATION	0.60053	0.60041	-0.00012
92	0	CORRELATION	0.60042	0.60032	-0.0001
93	0	CORRELATION	0.60007	0.59996	-0.00011
94	0	CORRELATION	0.60029	0.60019	-0.0001
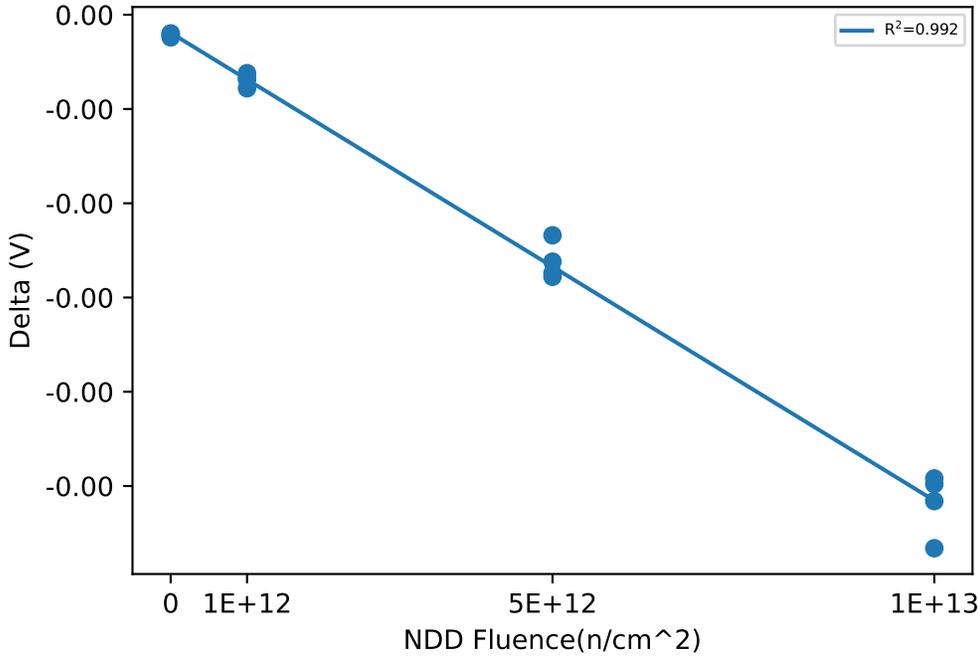
Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.60007	0.60033	0.60053	0.00019772	0.59996	0.60022	0.60041	0.00019545	-0.00012	-0.0001075	-0.0001	9.5743e-06
1e+12	0.60019	0.60037	0.60054	0.00016299	0.59988	0.60003	0.6002	0.00014306	-0.00039	-0.000345	-0.00031	3.3166e-05
5e+12	0.59999	0.60037	0.60054	0.00025826	0.5986	0.59907	0.5993	0.00031775	-0.00139	-0.00131	-0.00117	9.9331e-05
1e+13	0.59993	0.60019	0.60058	0.00027669	0.59728	0.5976	0.598	0.00030598	-0.00283	-0.00259	-0.00246	0.00016793
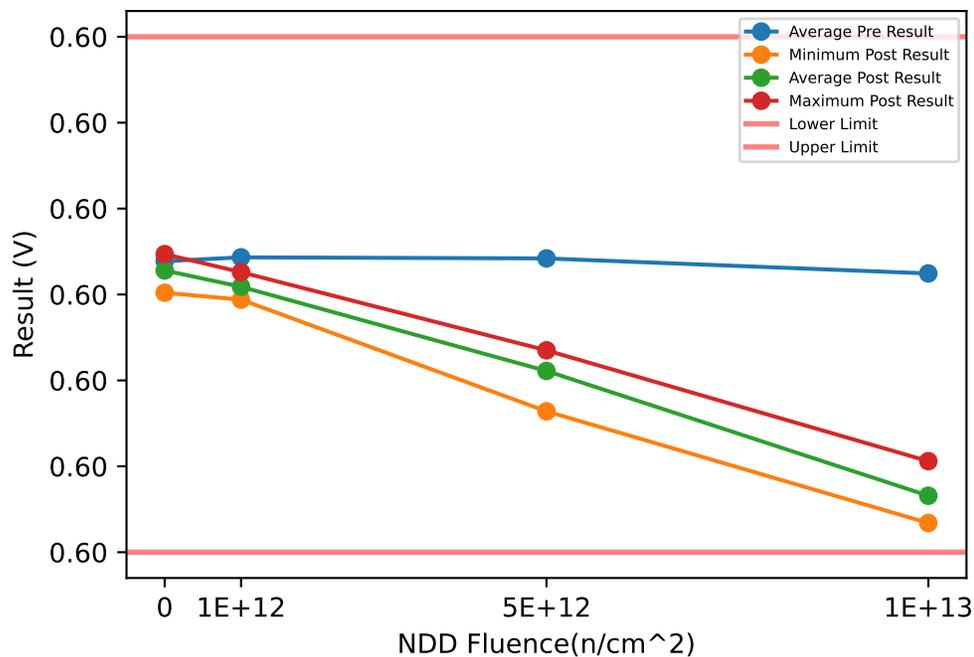
Device Test: 19.37 VOLTAGE|VREF//14/14/0/1000/5/500kHz//@VREF_25C

NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.6006	0.60026	-0.00034
2	1e+12	NDD	0.60055	0.60016	-0.00039
3	1e+12	NDD	0.60033	0.6	-0.00033
4	1e+12	NDD	0.60025	0.59994	-0.00031
5	5e+12	NDD	0.60054	0.59917	-0.00137
6	5e+12	NDD	0.60003	0.59864	-0.00139
7	5e+12	NDD	0.60051	0.59935	-0.00116
8	5e+12	NDD	0.6006	0.59928	-0.00132
9	1e+13	NDD	0.60063	0.59806	-0.00257
10	1e+13	NDD	0.60018	0.59734	-0.00284
11	1e+13	NDD	0.60018	0.5977	-0.00248
12	1e+13	NDD	0.59999	0.59753	-0.00246
91	0	CORRELATION	0.60058	0.60047	-0.00011
92	0	CORRELATION	0.6005	0.60039	-0.00011
93	0	CORRELATION	0.60012	0.60002	-0.0001
94	0	CORRELATION	0.60035	0.60024	-0.00011
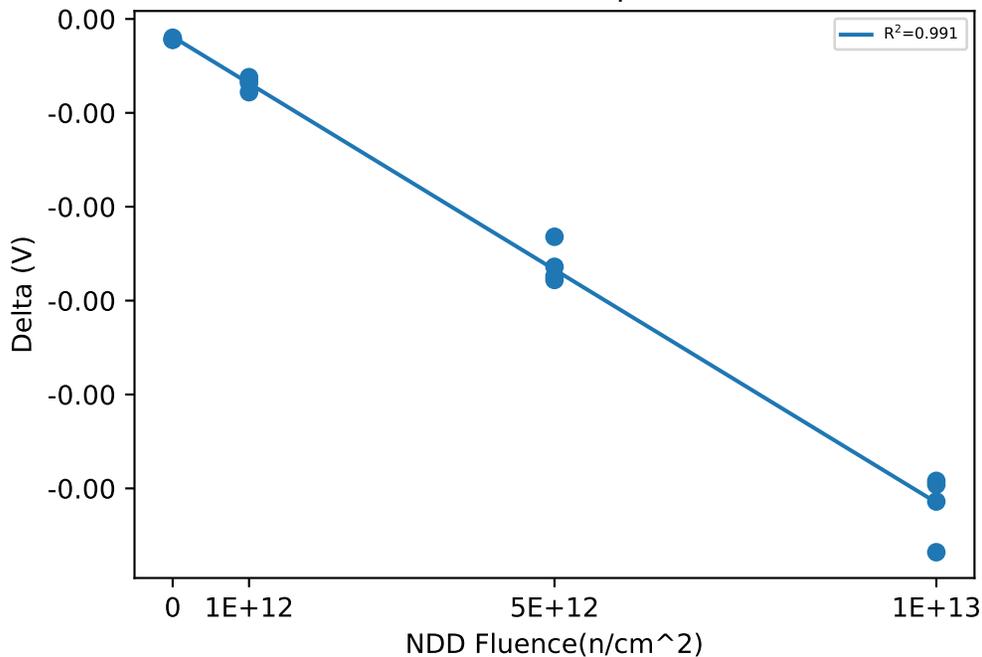
Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.60012	0.60039	0.60058	0.00020222	0.60002	0.60028	0.60047	0.00019782	-0.00011	-0.0001075	-0.0001	5e-06
1e+12	0.60025	0.60043	0.6006	0.00016899	0.59994	0.60009	0.60026	0.00014652	-0.00039	-0.0003425	-0.00031	3.4034e-05
5e+12	0.60003	0.60042	0.6006	0.00026268	0.59864	0.59911	0.59935	0.00032197	-0.00139	-0.00131	-0.00116	0.00010424
1e+13	0.59999	0.60025	0.60063	0.00027185	0.59734	0.59766	0.59806	0.00030598	-0.00284	-0.0025875	-0.00246	0.000175

Device Test: 19.39 LEVEL|TRANSCONDUCTANCE//8/8/0/0/5/500kHz//@EA_GM

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 1100.0, Upper Limit = 2700.0 (µA/V))

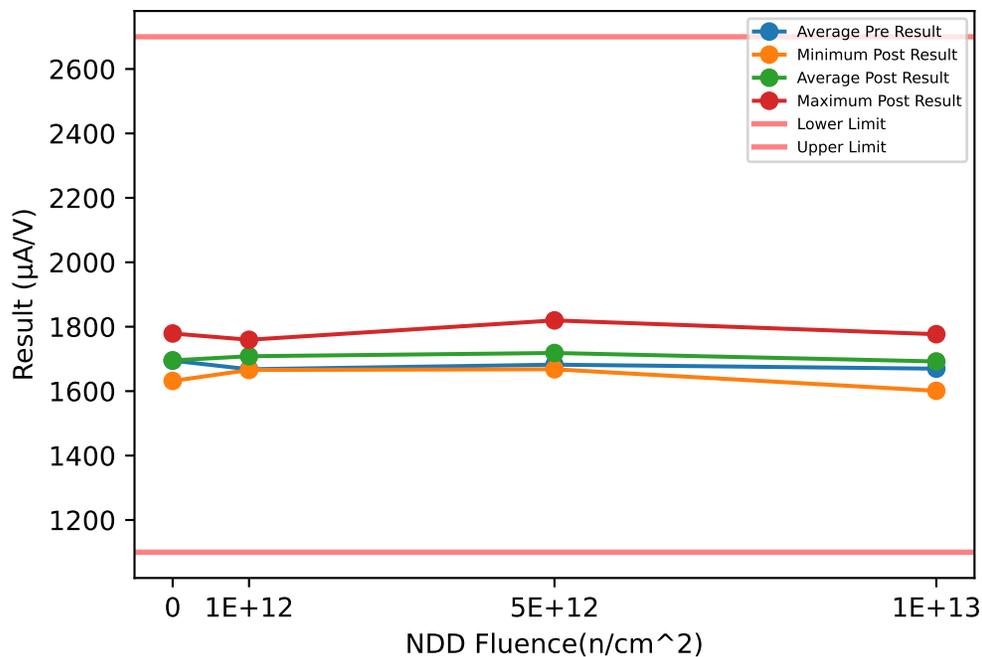| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1633.7	1665.6	31.992
2	1e+12	NDD	1667.9	1668	0.0829
3	1e+12	NDD	1685.8	1740.3	54.532
4	1e+12	NDD	1684.5	1759.5	75.002
5	5e+12	NDD	1633.7	1683.2	49.538
6	5e+12	NDD	1759.5	1819.6	60.093
7	5e+12	NDD	1685.8	1703.3	17.491
8	5e+12	NDD	1649.8	1667.9	18.107
9	1e+13	NDD	1759.3	1776.7	17.383
10	1e+13	NDD	1633.8	1650.8	16.928
11	1e+13	NDD	1601.5	1601.1	-0.4202
12	1e+13	NDD	1684.5	1740.4	55.875
91	0	CORRELATION	1685.2	1631.7	-53.586
92	0	CORRELATION	1650.7	1668	17.281
93	0	CORRELATION	1722	1779	56.951
94	0	CORRELATION	1720.7	1703.4	-17.365
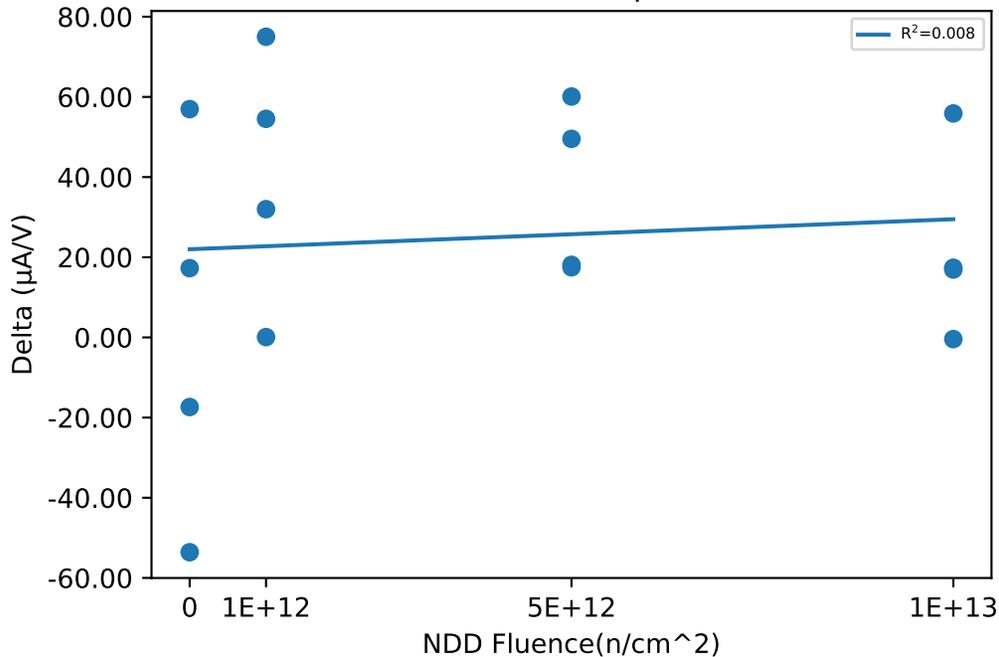
Test Statistics (µA/V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1650.7	1694.7	1722	33.916	1631.7	1695.5	1779	62.884	-53.586	0.81997	56.951	47.302
1e+12	1633.7	1668	1685.8	24.277	1665.6	1708.4	1759.5	48.625	0.0829	40.402	75.002	32.11
5e+12	1633.7	1682.2	1759.5	55.972	1667.9	1718.5	1819.6	68.954	17.491	36.307	60.093	21.803
1e+13	1601.5	1669.8	1759.3	68.774	1601.1	1692.2	1776.7	80.591	-0.4202	22.441	55.875	23.78

Device Test: 19.40 CURRENT|EA_SOURCE//8/8/0/0/5/500kHz//@EA_I_SOURCE

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 95.0, Upper Limit = 210.0 (μA))

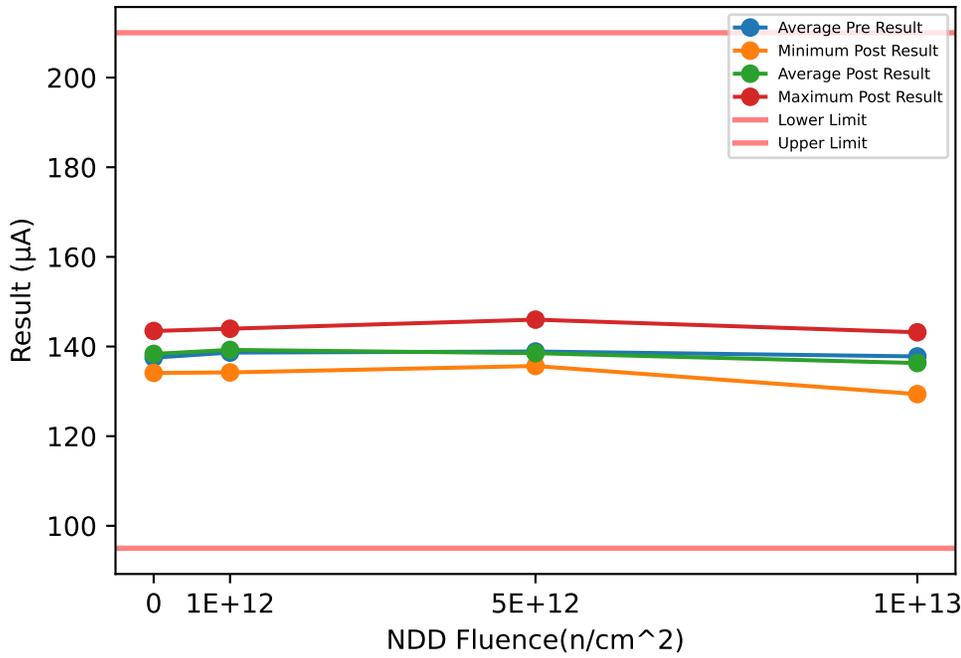| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	133.52	134.22	0.7052
2	1e+12	NDD	134.79	135.31	0.5257
3	1e+12	NDD	143.36	143.97	0.6113
4	1e+12	NDD	142.92	143.48	0.5606
5	5e+12	NDD	135.65	135.76	0.1075
6	5e+12	NDD	145.78	146	0.2125
7	5e+12	NDD	137.75	136.65	-1.1046
8	5e+12	NDD	136.38	135.66	-0.7244
9	1e+13	NDD	145.65	143.17	-2.4729
10	1e+13	NDD	132.68	131.76	-0.9141
11	1e+13	NDD	129.69	129.39	-0.3005
12	1e+13	NDD	143.17	140.93	-2.2348
91	0	CORRELATION	135.78	136.48	0.7043
92	0	CORRELATION	133.24	134.12	0.8755
93	0	CORRELATION	142.76	143.47	0.7069
94	0	CORRELATION	138.3	139.36	1.0651
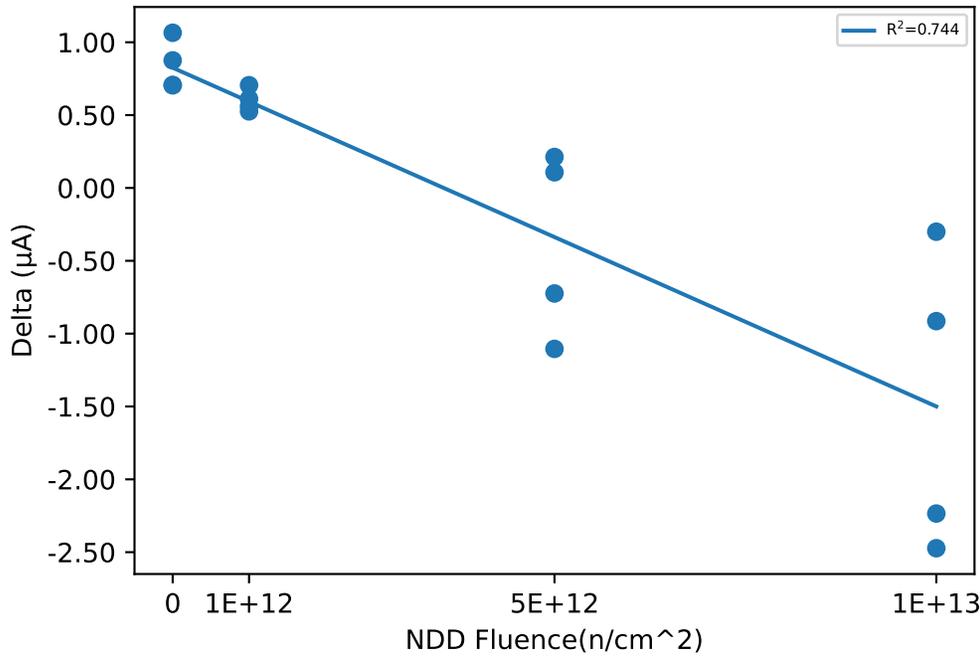
Test Statistics (μA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	133.24	137.52	142.76	4.0572	134.12	138.36	143.47	4.0247	0.7043	0.83795	1.0651	0.17131
1e+12	133.52	138.64	143.36	5.2166	134.22	139.25	143.97	5.1936	0.5257	0.6007	0.7052	0.078029
5e+12	135.65	138.89	145.78	4.6765	135.66	138.52	146	5.0079	-1.1046	-0.37725	0.2125	0.64092
1e+13	129.69	137.79	145.65	7.7985	129.39	136.31	143.17	6.7601	-2.4729	-1.4806	-0.3005	1.0436

Device Test: 19.41 CURRENT|EA_SINK//8/8/0/0/5/500kHz//@EA_I_SINK

## NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 95.0, Upper Limit = 210.0 (µA))

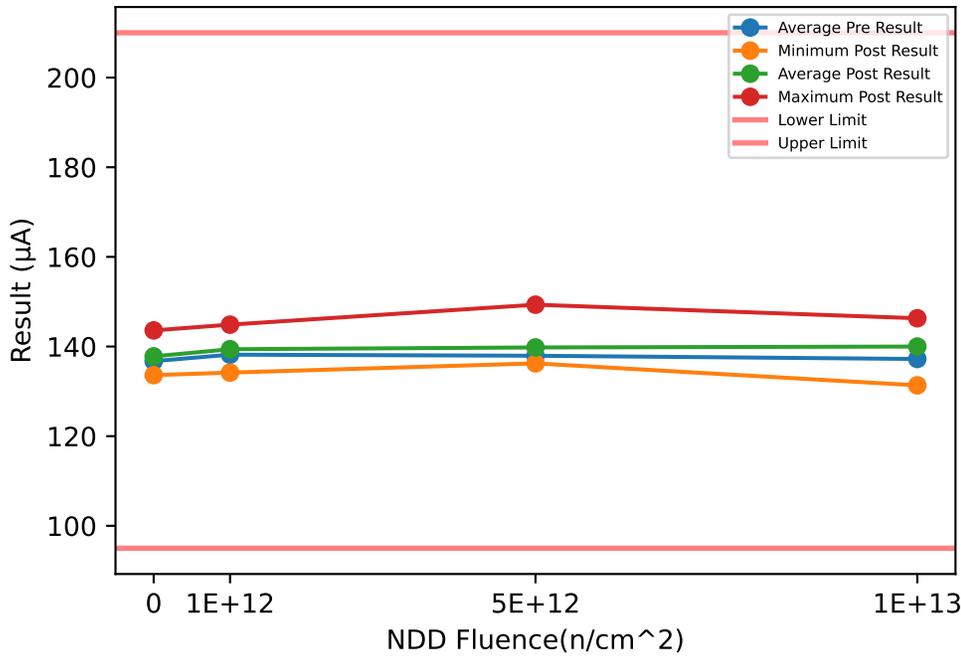| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	132.65	134.18	1.5333
2	1e+12	NDD	134.44	135.5	1.0592
3	1e+12	NDD	141.72	143.03	1.3162
4	1e+12	NDD	143.93	144.88	0.9523
5	5e+12	NDD	134.38	136.63	2.2551
6	5e+12	NDD	146.61	149.33	2.7227
7	5e+12	NDD	135.45	136.24	0.7963
8	5e+12	NDD	135.35	136.96	1.6155
9	1e+13	NDD	144.09	146.31	2.2193
10	1e+13	NDD	132.96	136.57	3.6086
11	1e+13	NDD	128.14	131.34	3.2015
12	1e+13	NDD	143.71	145.76	2.0518
91	0	CORRELATION	134.66	135.81	1.1554
92	0	CORRELATION	132.46	133.62	1.1589
93	0	CORRELATION	142.53	143.6	1.063
94	0	CORRELATION	137.3	138.19	0.8923
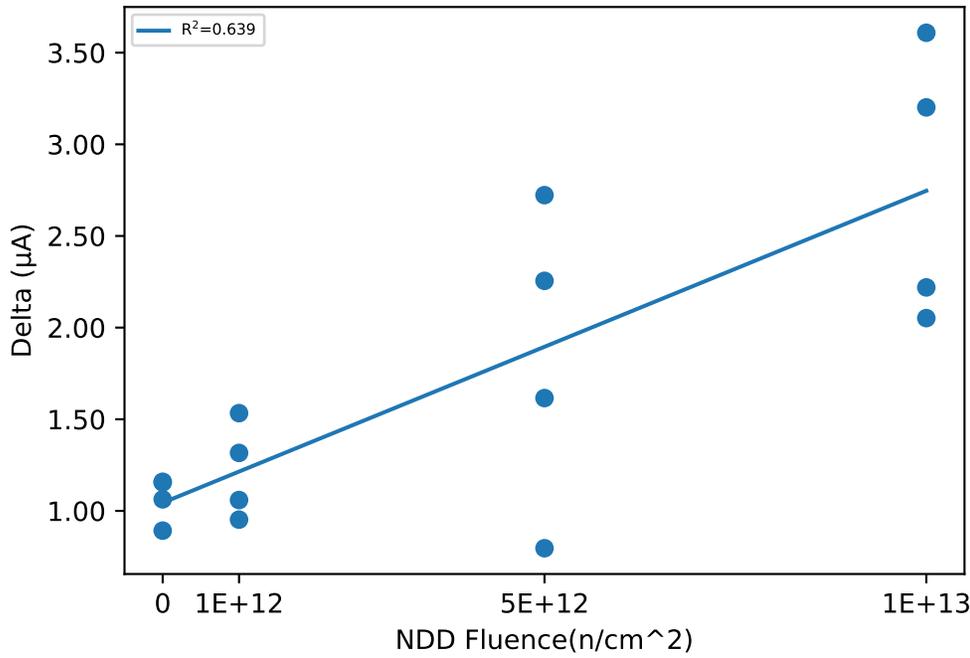
Test Statistics (µA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	132.46	136.74	142.53	4.3413	133.62	137.8	143.6	4.2892	0.8923	1.0674	1.1589	0.12489
1e+12	132.65	138.18	143.93	5.4797	134.18	139.4	144.88	5.3425	0.9523	1.2153	1.5333	0.26131
5e+12	134.38	137.94	146.61	5.7955	136.24	139.79	149.33	6.3657	0.7963	1.8474	2.7227	0.83486
1e+13	128.14	137.22	144.09	7.9542	131.34	139.99	146.31	7.2953	2.0518	2.7703	3.6086	0.75466
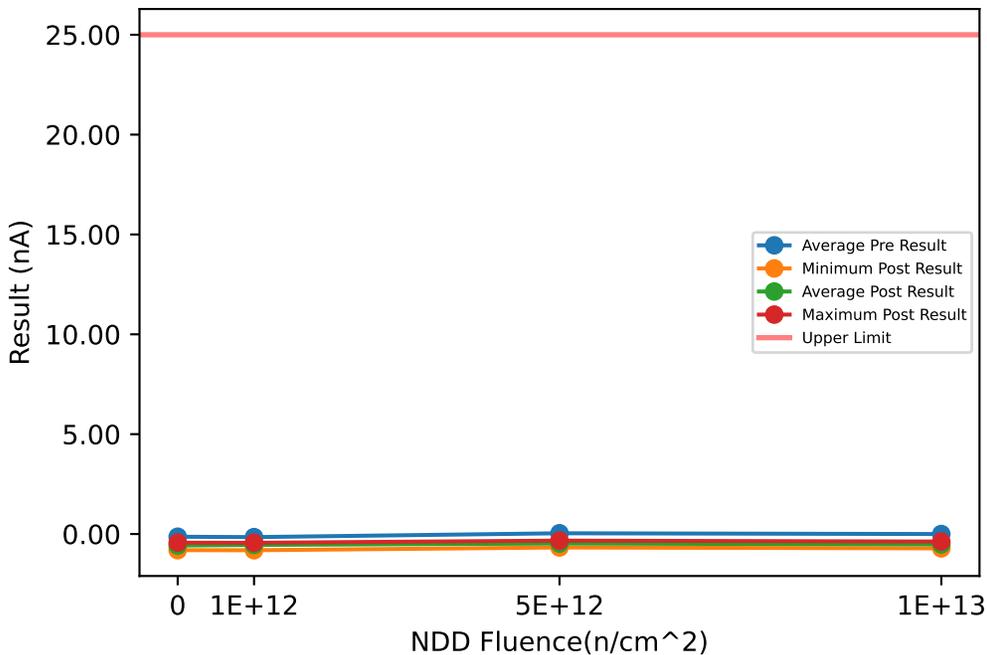
Device Test: 19.42 CURRENT|EA//8/8/0/0/5/500kHz//@EA_IB

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 25.0 (nA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.1435	-0.8123	-0.9558
2	1e+12	NDD	0.0343	-0.44	-0.4743
3	1e+12	NDD	-0.4807	-0.44	0.0407
4	1e+12	NDD	-0.3207	-0.4962	-0.1755
5	5e+12	NDD	0.3963	-0.6748	-1.0711
6	5e+12	NDD	0.1155	-0.5304	-0.6459
7	5e+12	NDD	0	-0.3308	-0.3308
8	5e+12	NDD	-0.3643	-0.3682	-0.0039
9	1e+13	NDD	0.3557	-0.7185	-1.0742
10	1e+13	NDD	-0.0281	-0.4649	-0.4368
11	1e+13	NDD	0.025	-0.5181	-0.5431
12	1e+13	NDD	-0.3581	-0.3776	-0.0195
91	0	CORRELATION	0.181	-0.8091	-0.9901
92	0	CORRELATION	-0.0406	-0.5211	-0.4805
93	0	CORRELATION	-0.3215	-0.5462	-0.2247
94	0	CORRELATION	-0.3643	-0.4337	-0.0694
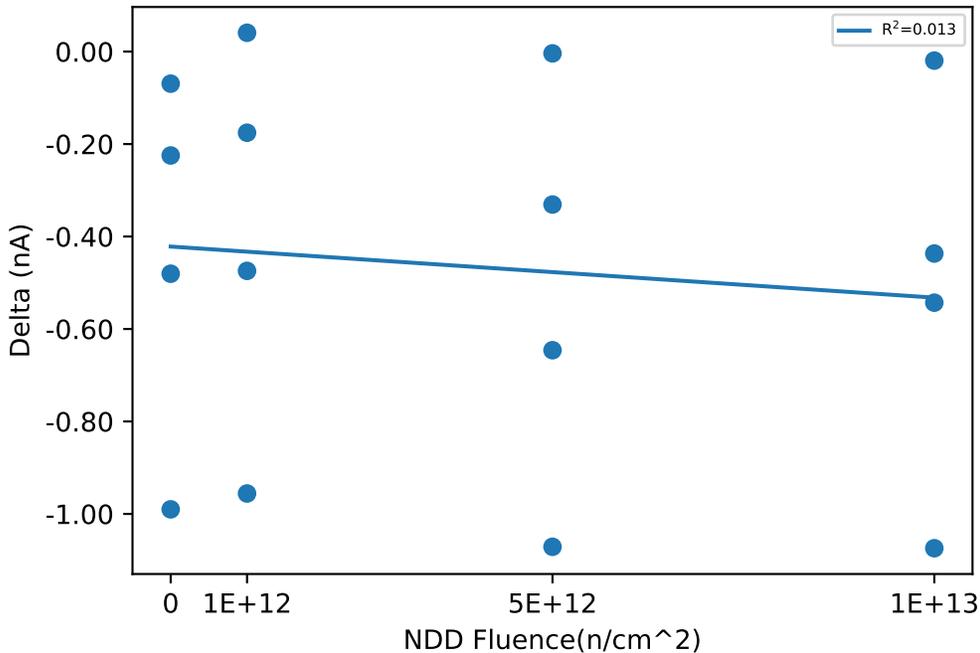
Test Statistics (nA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.3643	-0.13635	0.181	0.25568	-0.8091	-0.57753	-0.4337	0.16174	-0.9901	-0.44117	-0.0694	0.4033
1e+12	-0.4807	-0.1559	0.1435	0.29352	-0.8123	-0.54712	-0.44	0.17876	-0.9558	-0.39122	0.0407	0.43156
5e+12	-0.3643	0.036875	0.3963	0.315	-0.6748	-0.47605	-0.3308	0.15831	-1.0711	-0.51292	-0.0039	0.45516
1e+13	-0.3581	-0.001375	0.3557	0.29221	-0.7185	-0.51977	-0.3776	0.14459	-1.0742	-0.5184	-0.0195	0.43401

Device Test: 19.43 CURRENT|EA//8/8/0/0/5/100kHz//@EA_IB

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 25.0 (nA))

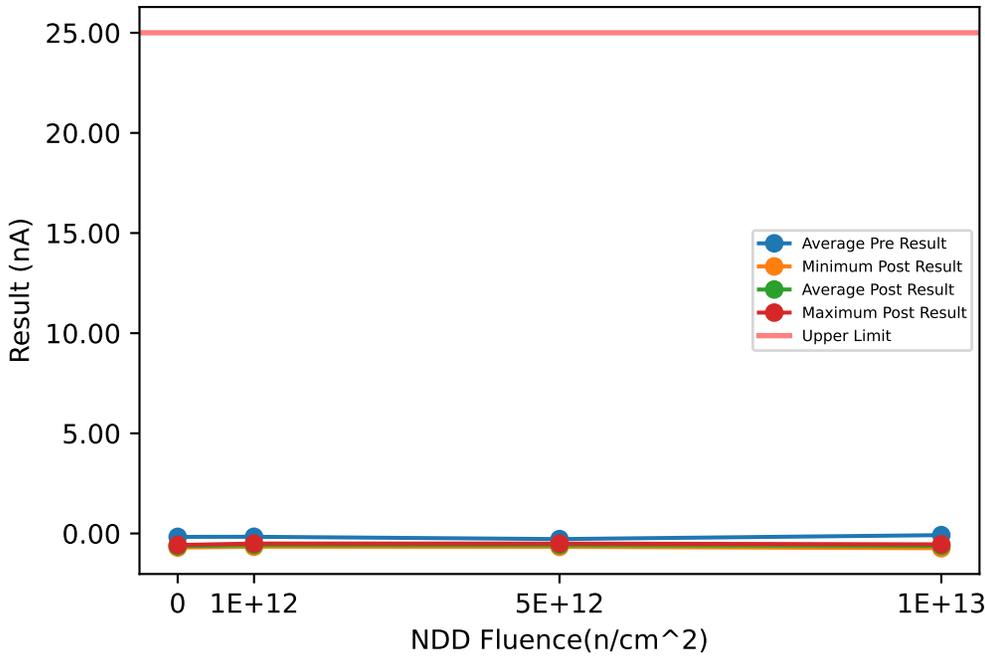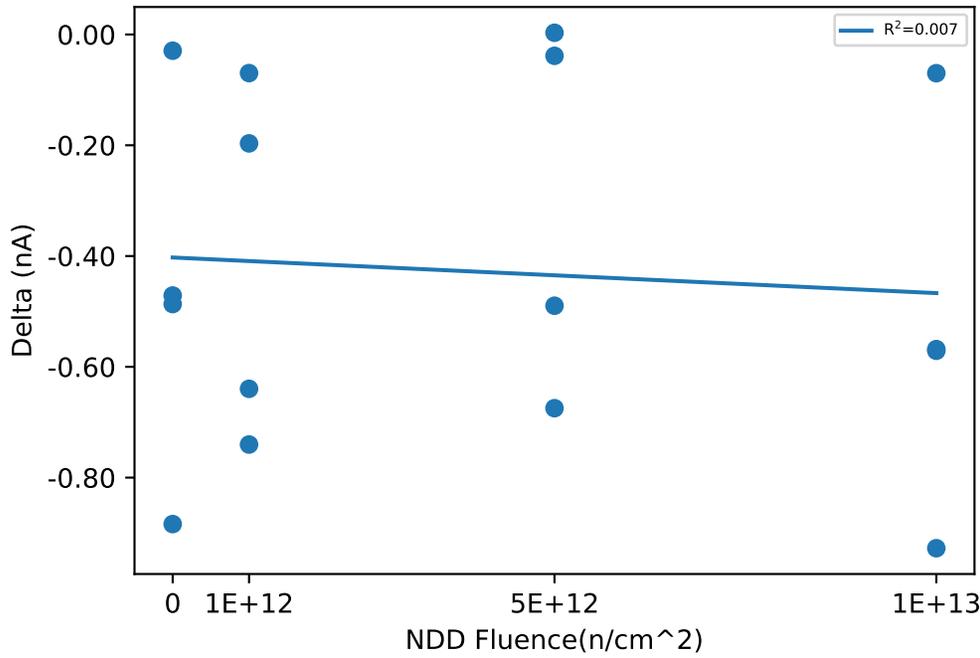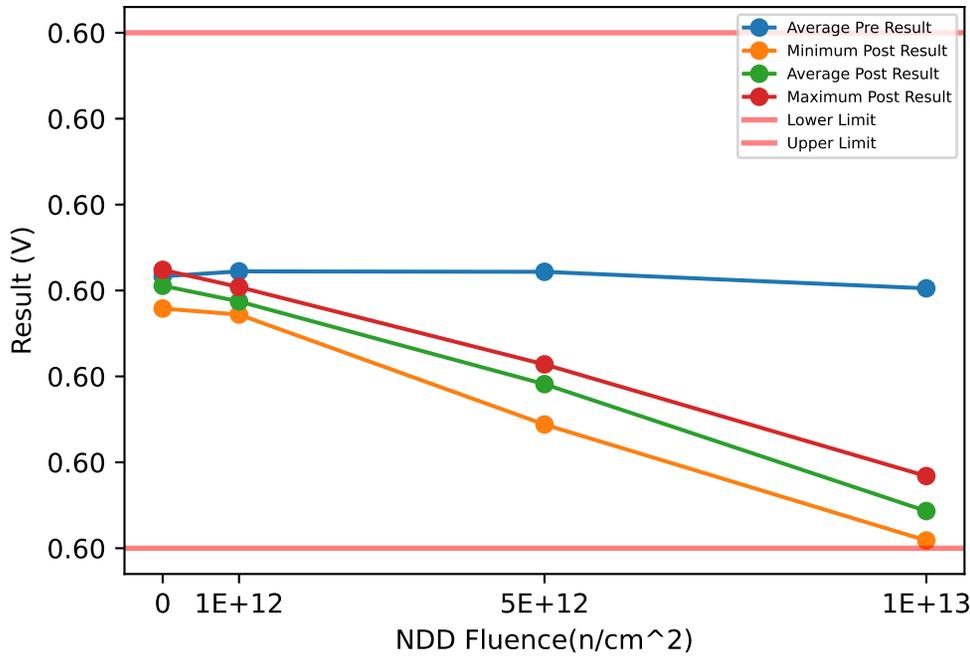| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.078	-0.6623	-0.7403
2	1e+12	NDD	0.0281	-0.6116	-0.6397
3	1e+12	NDD	-0.3059	-0.5025	-0.1966
4	1e+12	NDD	-0.4577	-0.5274	-0.0697
5	5e+12	NDD	0.0062	-0.6685	-0.6747
6	5e+12	NDD	-0.1343	-0.624	-0.4897
7	5e+12	NDD	-0.5056	-0.5025	0.0031
8	5e+12	NDD	-0.4826	-0.5211	-0.0385
9	1e+13	NDD	0.3433	-0.5842	-0.9275
10	1e+13	NDD	0.0281	-0.5429	-0.571
11	1e+13	NDD	-0.1685	-0.7365	-0.568
12	1e+13	NDD	-0.5324	-0.6023	-0.0699
91	0	CORRELATION	0.181	-0.7029	-0.8839
92	0	CORRELATION	-0.1436	-0.6303	-0.4867
93	0	CORRELATION	-0.1685	-0.6398	-0.4713
94	0	CORRELATION	-0.5449	-0.5742	-0.0293

Test Statistics (nA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.5449	-0.169	0.181	0.2969	-0.7029	-0.6368	-0.5742	0.052723	-0.8839	-0.4678	-0.0293	0.34919
1e+12	-0.4577	-0.16437	0.078	0.2594	-0.6623	-0.57595	-0.5025	0.074115	-0.7403	-0.41157	-0.0697	0.32822
5e+12	-0.5056	-0.27908	0.0062	0.255	-0.6685	-0.57903	-0.5025	0.080083	-0.6747	-0.29995	0.0031	0.33498
1e+13	-0.5324	-0.082375	0.3433	0.36667	-0.7365	-0.61647	-0.5429	0.083789	-0.9275	-0.5341	-0.0699	0.35249

Device Test: 19.44 VOLTAGE|VREF//8/8/0/0/5/100kHz//@VREF_25C

NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.60038	0.60004	-0.00034
2	1e+12	NDD	0.60032	0.59994	-0.00038
3	1e+12	NDD	0.60014	0.59979	-0.00035
4	1e+12	NDD	0.60005	0.59972	-0.00033
5	5e+12	NDD	0.60035	0.59898	-0.00137
6	5e+12	NDD	0.59983	0.59844	-0.00139
7	5e+12	NDD	0.60031	0.59914	-0.00117
8	5e+12	NDD	0.60038	0.59908	-0.0013
9	1e+13	NDD	0.60042	0.59784	-0.00258
10	1e+13	NDD	0.59993	0.59709	-0.00284
11	1e+13	NDD	0.59998	0.59749	-0.00249
12	1e+13	NDD	0.59977	0.59731	-0.00246
91	0	CORRELATION	0.60037	0.60024	-0.00013
92	0	CORRELATION	0.60026	0.60016	-0.0001
93	0	CORRELATION	0.5999	0.59979	-0.00011
94	0	CORRELATION	0.60013	0.60003	-0.0001
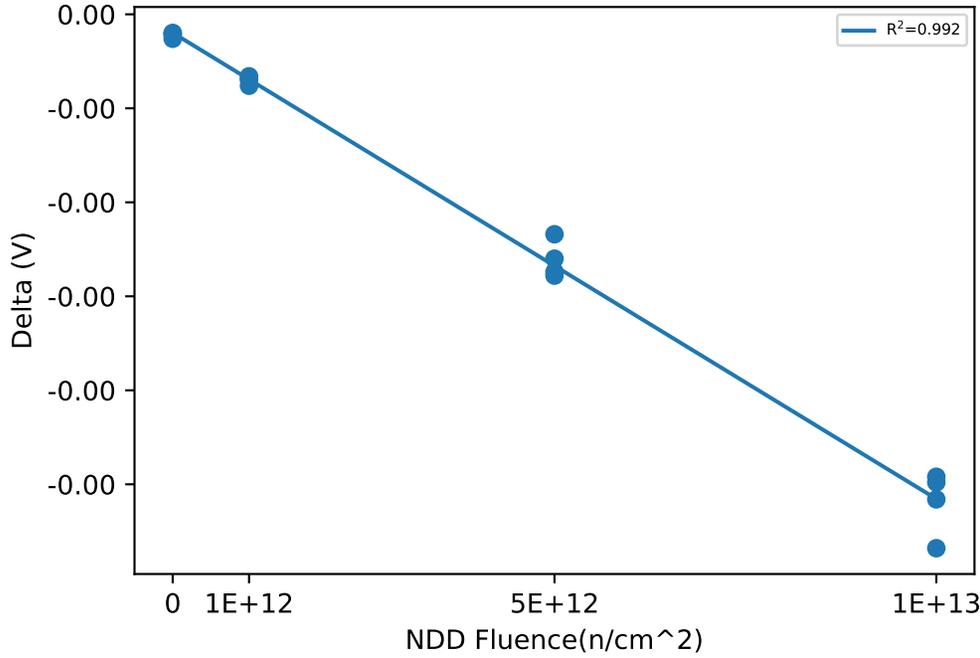
Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5999	0.60017	0.60037	0.00020207	0.59979	0.60006	0.60024	0.00019672	-0.00013	-0.00011	-0.0001	1.4142e-05
1e+12	0.60005	0.60022	0.60038	0.0001537	0.59972	0.59987	0.60004	0.00014454	-0.00038	-0.00035	-0.00033	2.1602e-05
5e+12	0.59983	0.60022	0.60038	0.00025992	0.59844	0.59891	0.59914	0.00032021	-0.00139	-0.0013075	-0.00117	9.9457e-05
1e+13	0.59977	0.60003	0.60042	0.00027815	0.59709	0.59743	0.59784	0.00031711	-0.00284	-0.0025925	-0.00246	0.0001727
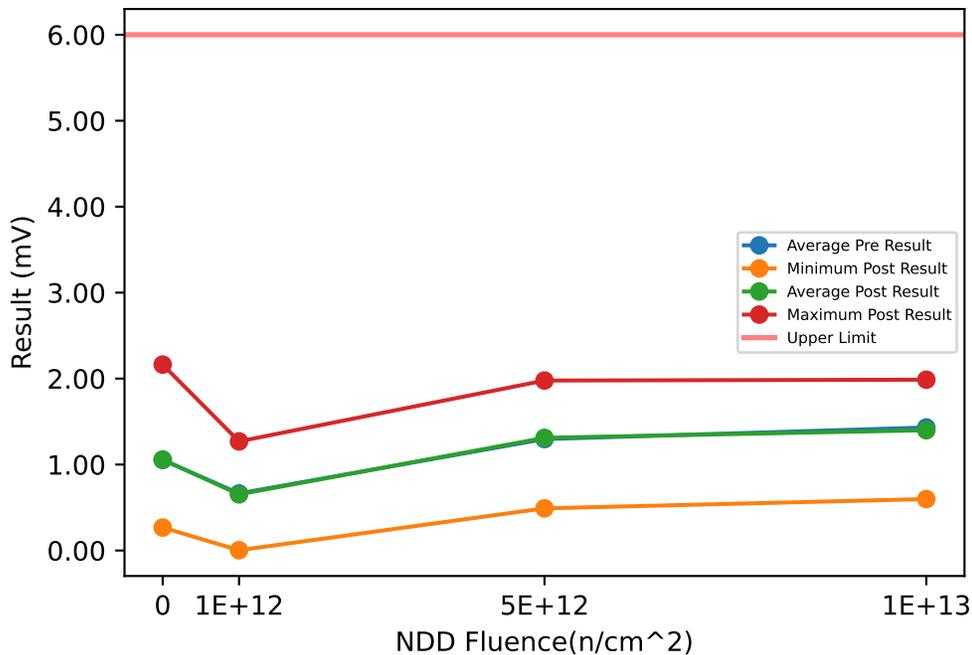
Device Test: 19.46 VOLTAGE|OFFSET//8/8/0/0/5/100kHz//@EA_OS

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 6.0 (mV))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.7618	0.7423	-0.0195
2	1e+12	NDD	0.6203	0.5966	-0.0237
3	1e+12	NDD	1.2886	1.2692	-0.0194
4	1e+12	NDD	-0.015	0.0033	0.0183
5	5e+12	NDD	1.6045	1.5804	-0.0241
6	5e+12	NDD	0.4406	0.4903	0.0497
7	5e+12	NDD	1.9538	1.9775	0.0237
8	5e+12	NDD	1.1857	1.1955	0.0098
9	1e+13	NDD	1.6622	1.6048	-0.0574
10	1e+13	NDD	0.6377	0.5983	-0.0394
11	1e+13	NDD	2.0251	1.9872	-0.0379
12	1e+13	NDD	1.4002	1.4065	0.0063
91	0	CORRELATION	2.1675	2.163	-0.0045
92	0	CORRELATION	0.6307	0.6405	0.0098
93	0	CORRELATION	0.2666	0.2671	0.0005
94	0	CORRELATION	1.1485	1.1643	0.0158
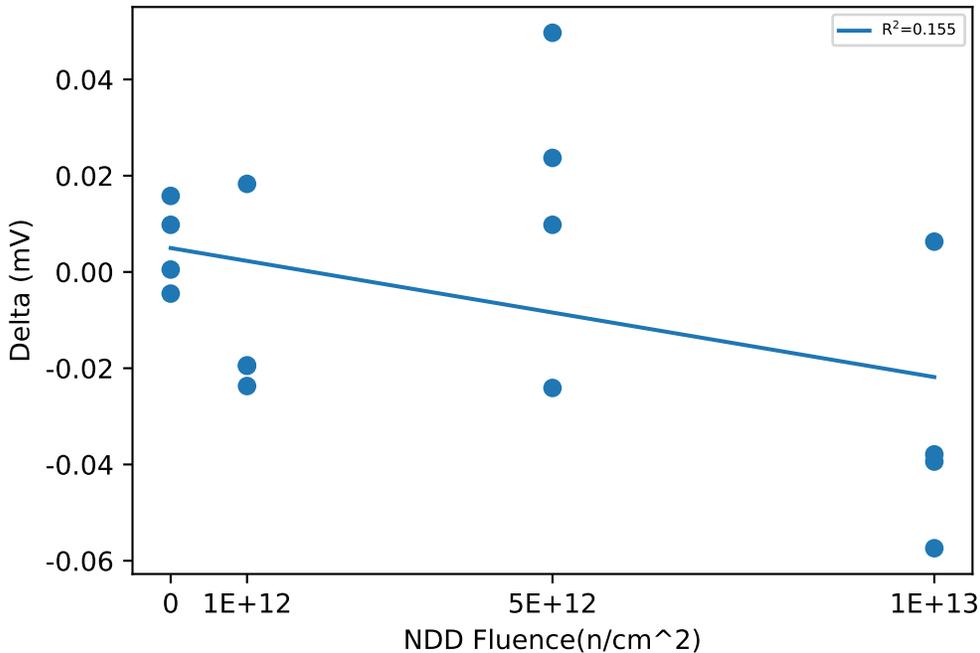
Test Statistics (mV)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.2666	1.0533	2.1675	0.82623	0.2671	1.0587	2.163	0.82303	-0.0045	0.0054	0.0158	0.0091203
1e+12	-0.015	0.66392	1.2886	0.53623	0.0033	0.65285	1.2692	0.52057	-0.0237	-0.011075	0.0183	0.019686
5e+12	0.4406	1.2961	1.9538	0.65109	0.4903	1.3109	1.9775	0.63343	-0.0241	0.014775	0.0497	0.030743
1e+13	0.6377	1.4313	2.0251	0.58784	0.5983	1.3992	1.9872	0.58581	-0.0574	-0.0321	0.0063	0.02709
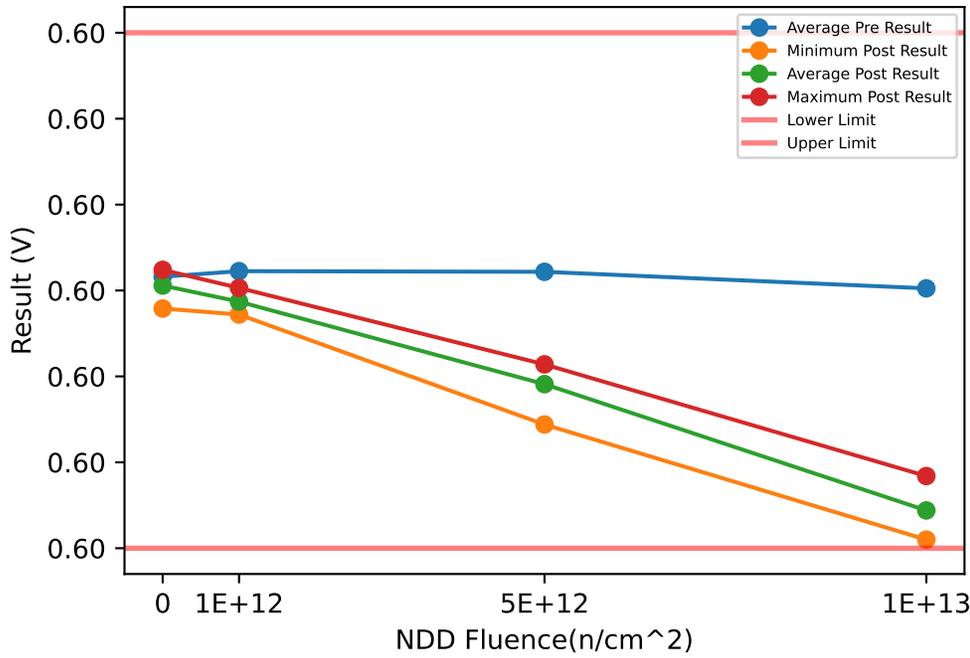
Device Test: 19.47 VOLTAGE|VREF//8/8/0/0/5/500kHz//@VREF_25C

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.60039	0.60003	-0.00036
2	1e+12	NDD	0.60033	0.59994	-0.00039
3	1e+12	NDD	0.60014	0.59979	-0.00035
4	1e+12	NDD	0.60004	0.59972	-0.00032
5	5e+12	NDD	0.60034	0.59898	-0.00136
6	5e+12	NDD	0.59984	0.59844	-0.0014
7	5e+12	NDD	0.60031	0.59914	-0.00117
8	5e+12	NDD	0.60038	0.59908	-0.0013
9	1e+13	NDD	0.60041	0.59784	-0.00257
10	1e+13	NDD	0.59993	0.5971	-0.00283
11	1e+13	NDD	0.59998	0.5975	-0.00248
12	1e+13	NDD	0.59978	0.59732	-0.00246
91	0	CORRELATION	0.60036	0.60024	-0.00012
92	0	CORRELATION	0.60026	0.60016	-0.0001
93	0	CORRELATION	0.59989	0.59979	-0.0001
94	0	CORRELATION	0.60013	0.60004	-9e-05
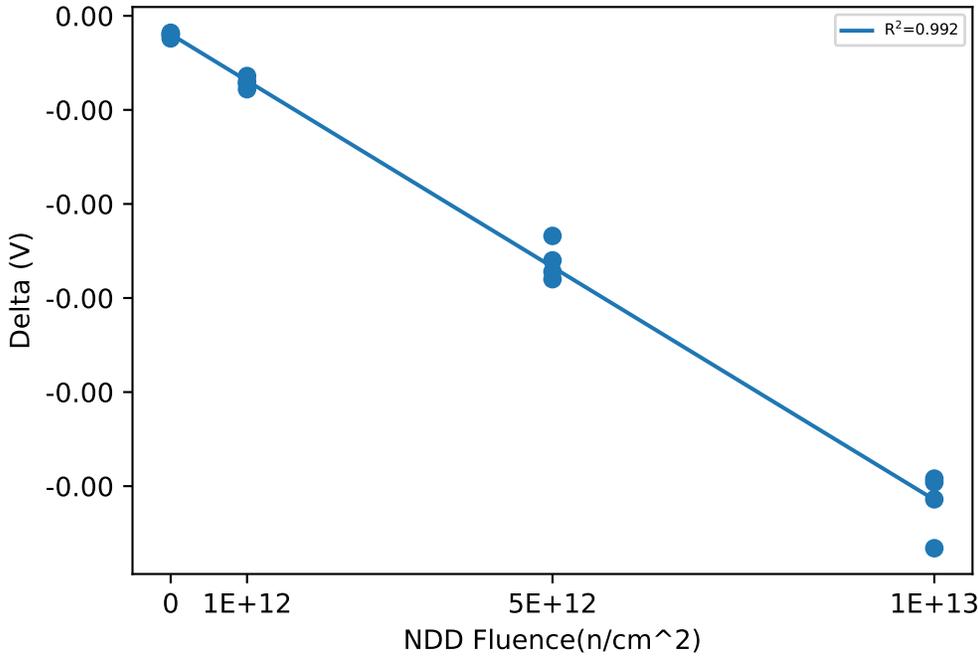
Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.59989	0.60016	0.60036	0.00020314	0.59979	0.60006	0.60024	0.00019636	-0.00012	-0.0001025	-9e-05	1.2583e-05
1e+12	0.60004	0.60023	0.60039	0.00016299	0.59972	0.59987	0.60003	0.00014071	-0.00039	-0.000355	-0.00032	2.8868e-05
5e+12	0.59984	0.60022	0.60038	0.00025329	0.59844	0.59891	0.59914	0.00032021	-0.0014	-0.0013075	-0.00117	0.00010046
1e+13	0.59978	0.60003	0.60041	0.00027037	0.5971	0.59744	0.59784	0.00031284	-0.00283	-0.002585	-0.00246	0.0001702
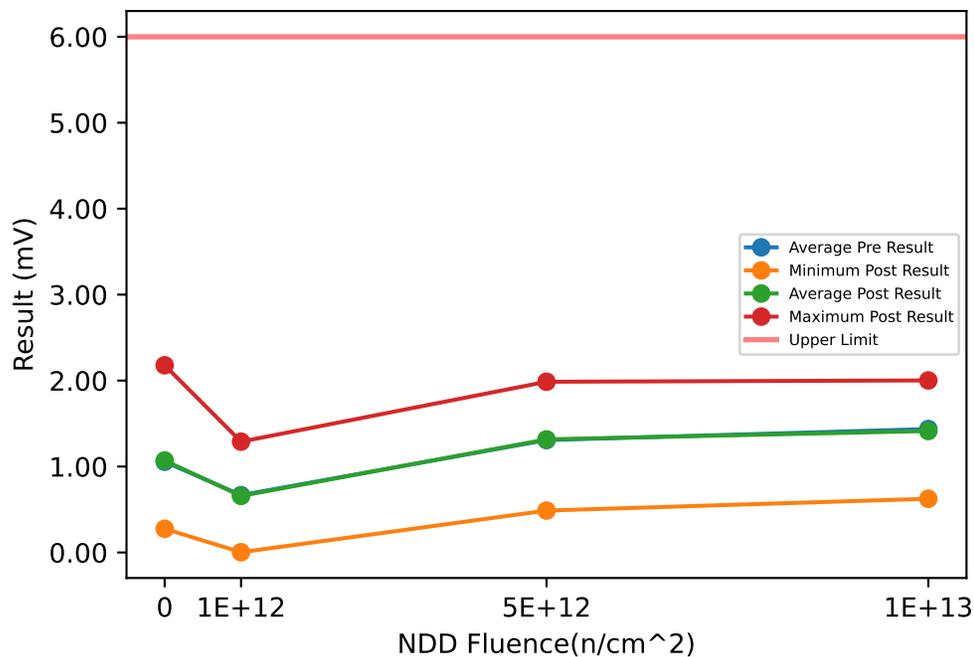
Device Test: 19.49 VOLTAGE|OFFSET//8/8/0/0/5/500kHz//@EA_OS

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 6.0 (mV))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.7665	0.7407	-0.0258
2	1e+12	NDD	0.6291	0.5987	-0.0304
3	1e+12	NDD	1.2847	1.2895	0.0048
4	1e+12	NDD	-0.0106	0.0031	0.0137
5	5e+12	NDD	1.6155	1.5873	-0.0282
6	5e+12	NDD	0.4528	0.4875	0.0347
7	5e+12	NDD	1.9695	1.9864	0.0169
8	5e+12	NDD	1.1934	1.2027	0.0093
9	1e+13	NDD	1.6617	1.6114	-0.0503
10	1e+13	NDD	0.648	0.6251	-0.0229
11	1e+13	NDD	2.0246	2.002	-0.0226
12	1e+13	NDD	1.4111	1.4139	0.0028
91	0	CORRELATION	2.162	2.1779	0.0159
92	0	CORRELATION	0.6397	0.6483	0.0086
93	0	CORRELATION	0.2685	0.2758	0.0073
94	0	CORRELATION	1.1522	1.1792	0.027
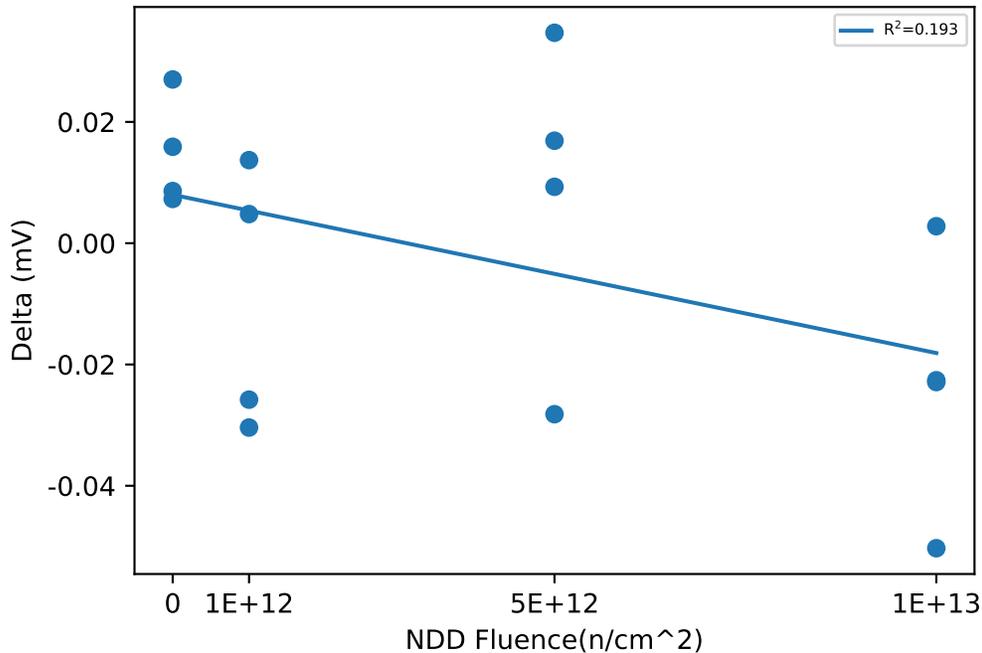
Test Statistics (mV)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.2685	1.0556	2.162	0.82178	0.2758	1.0703	2.1779	0.82623	0.0073	0.0147	0.027	0.0090314
1e+12	-0.0106	0.66742	1.2847	0.53293	0.0031	0.658	1.2895	0.52853	-0.0304	-0.009425	0.0137	0.021948
5e+12	0.4528	1.3078	1.9695	0.65234	0.4875	1.316	1.9864	0.6383	-0.0282	0.008175	0.0347	0.026483
1e+13	0.648	1.4364	2.0246	0.5828	0.6251	1.4131	2.002	0.57939	-0.0503	-0.02325	0.0028	0.021686

Device Test: 19.50 VOLTAGE|VREF//8/8/0/1000/5/100kHz//@VREF_25C

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

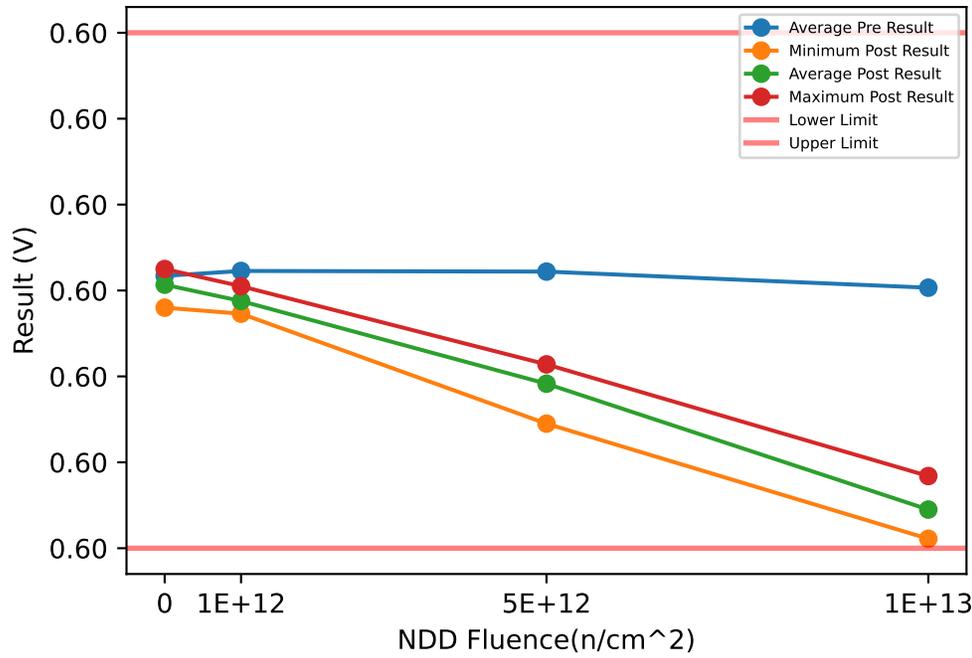| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.60039	0.60005	-0.00034
2	1e+12	NDD	0.60033	0.59994	-0.00039
3	1e+12	NDD	0.60014	0.59979	-0.00035
4	1e+12	NDD	0.60005	0.59973	-0.00032
5	5e+12	NDD	0.60035	0.59899	-0.00136
6	5e+12	NDD	0.59983	0.59845	-0.00138
7	5e+12	NDD	0.60031	0.59914	-0.00117
8	5e+12	NDD	0.60039	0.59908	-0.00131
9	1e+13	NDD	0.60042	0.59784	-0.00258
10	1e+13	NDD	0.59994	0.59711	-0.00283
11	1e+13	NDD	0.59999	0.59751	-0.00248
12	1e+13	NDD	0.59978	0.59734	-0.00244
91	0	CORRELATION	0.60037	0.60025	-0.00012
92	0	CORRELATION	0.60026	0.60017	-9e-05
93	0	CORRELATION	0.59991	0.5998	-0.00011
94	0	CORRELATION	0.60014	0.60005	-9e-05
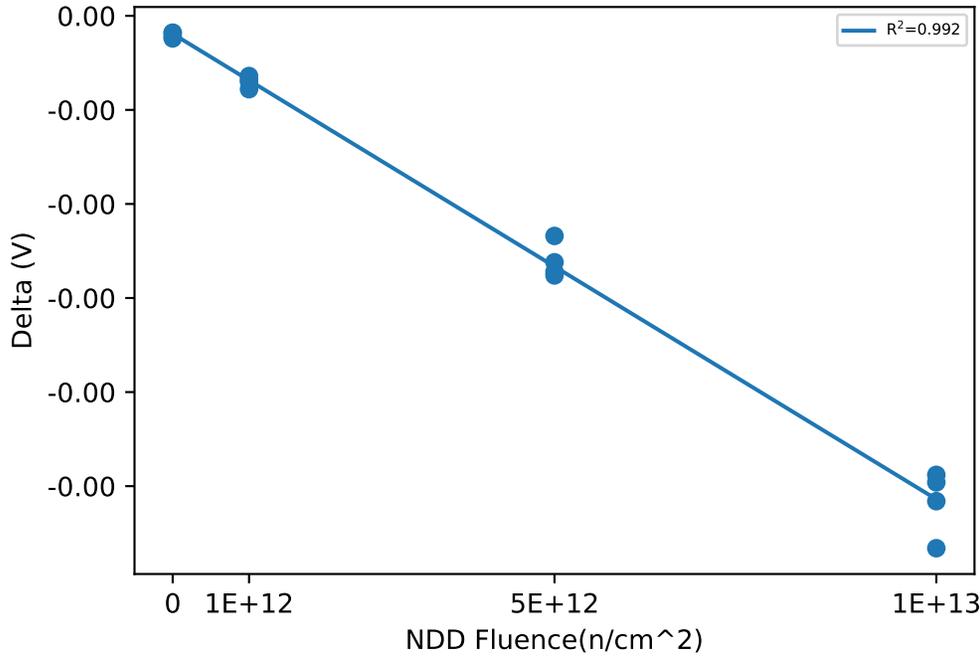
Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.59991	0.60017	0.60037	0.00019715	0.5998	0.60007	0.60025	0.00019636	-0.00012	-0.0001025	-9e-05	1.5e-05
1e+12	0.60005	0.60023	0.60039	0.00015924	0.59973	0.59988	0.60005	0.000145	-0.00039	-0.00035	-0.00032	2.9439e-05
5e+12	0.59983	0.60022	0.60039	0.00026204	0.59845	0.59891	0.59914	0.00031607	-0.00138	-0.001305	-0.00117	9.4692e-05
1e+13	0.59978	0.60003	0.60042	0.00027342	0.59711	0.59745	0.59784	0.00030735	-0.00283	-0.0025825	-0.00244	0.00017519
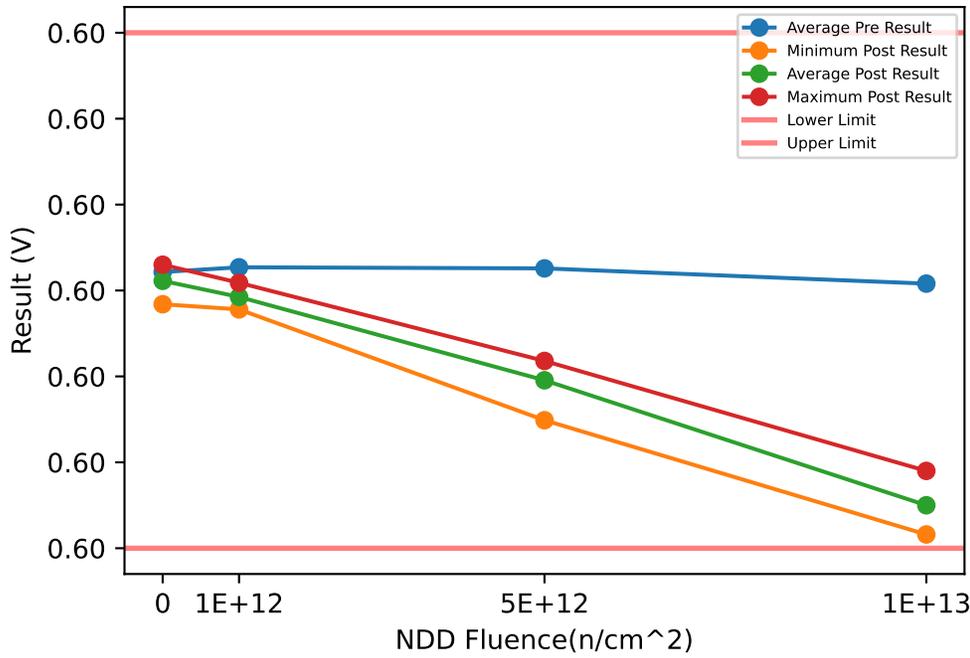
Device Test: 19.52 VOLTAGE|VREF//8/8/0/1000/5/500kHz//@VREF_25C

NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.60043	0.60009	-0.00034
2	1e+12	NDD	0.60038	0.59999	-0.00039
3	1e+12	NDD	0.60018	0.59984	-0.00034
4	1e+12	NDD	0.60009	0.59978	-0.00031
5	5e+12	NDD	0.60038	0.59903	-0.00135
6	5e+12	NDD	0.59989	0.59849	-0.0014
7	5e+12	NDD	0.60034	0.59918	-0.00116
8	5e+12	NDD	0.60042	0.59912	-0.0013
9	1e+13	NDD	0.60046	0.5979	-0.00256
10	1e+13	NDD	0.6	0.59716	-0.00284
11	1e+13	NDD	0.60003	0.59755	-0.00248
12	1e+13	NDD	0.59983	0.59739	-0.00244
91	0	CORRELATION	0.60043	0.6003	-0.00013
92	0	CORRELATION	0.60031	0.60021	-0.0001
93	0	CORRELATION	0.59994	0.59984	-0.0001
94	0	CORRELATION	0.60018	0.6001	-8e-05
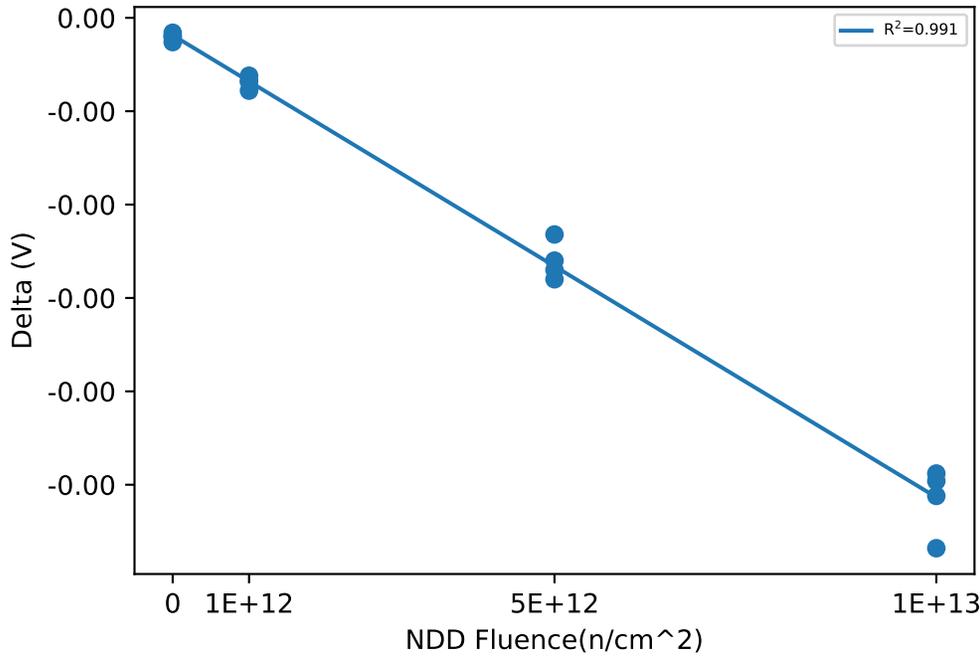
Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.59994	0.60022	0.60043	0.00020984	0.59984	0.60011	0.6003	0.00019923	-0.00013	-0.0001025	-8e-05	2.0616e-05
1e+12	0.60009	0.60027	0.60043	0.00016145	0.59978	0.59993	0.60009	0.00014107	-0.00039	-0.000345	-0.00031	3.3166e-05
5e+12	0.59989	0.60026	0.60042	0.00024717	0.59849	0.59896	0.59918	0.00031607	-0.0014	-0.0013025	-0.00116	0.0001034
1e+13	0.59983	0.60008	0.60046	0.0002682	0.59716	0.5975	0.5979	0.00031102	-0.00284	-0.00258	-0.00244	0.00018037
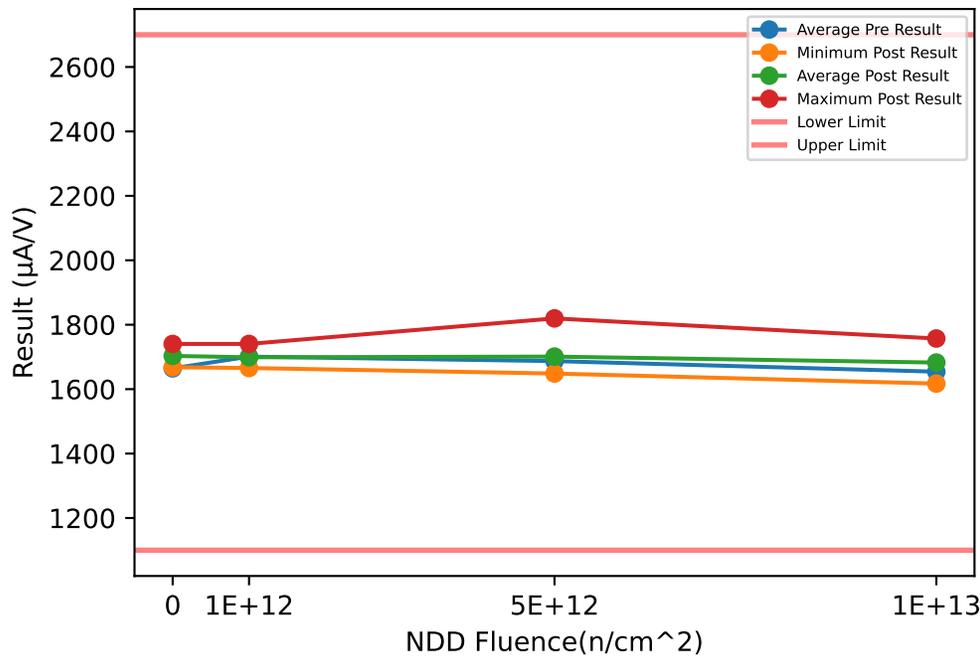
Device Test: 19.9 LEVEL|TRANSCONDUCTANCE//12/12/0/0/5/500kHz//@EA_GM

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 1100.0, Upper Limit = 2700.0 (μA/V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1617.2	1665.7	48.495
2	1e+12	NDD	1667.9	1668	0.0829
3	1e+12	NDD	1740.7	1721.6	-19.149
4	1e+12	NDD	1778.1	1740.4	-37.702
5	5e+12	NDD	1633.7	1648.5	14.824
6	5e+12	NDD	1779.1	1819.6	40.539
7	5e+12	NDD	1685.8	1650.6	-35.186
8	5e+12	NDD	1649.8	1685.4	35.641
9	1e+13	NDD	1721.5	1757.2	35.699
10	1e+13	NDD	1601.2	1633.9	32.762
11	1e+13	NDD	1554.8	1617.2	62.402
12	1e+13	NDD	1739.4	1721.7	-17.752
91	0	CORRELATION	1601	1701.1	100.1
92	0	CORRELATION	1650.7	1668	17.289
93	0	CORRELATION	1722	1740.3	18.282
94	0	CORRELATION	1684.5	1703.4	18.864
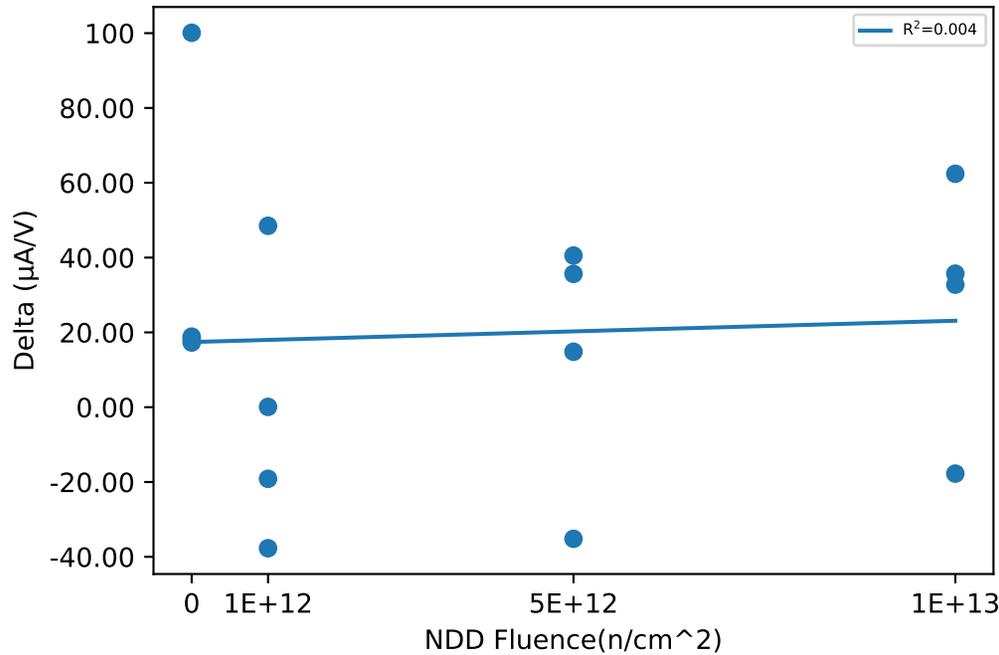
Test Statistics (μA/V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1601	1664.5	1722	51.426	1668	1703.2	1740.3	29.567	17.289	38.634	100.1	40.982
1e+12	1617.2	1701	1778.1	72.222	1665.7	1698.9	1740.4	37.852	-37.702	-2.0681	48.495	37.071
5e+12	1633.7	1687.1	1779.1	65.086	1648.5	1701	1819.6	80.848	-35.186	13.955	40.539	34.605
1e+13	1554.8	1654.2	1739.4	90.325	1617.2	1682.5	1757.2	67.649	-17.752	28.278	62.402	33.458
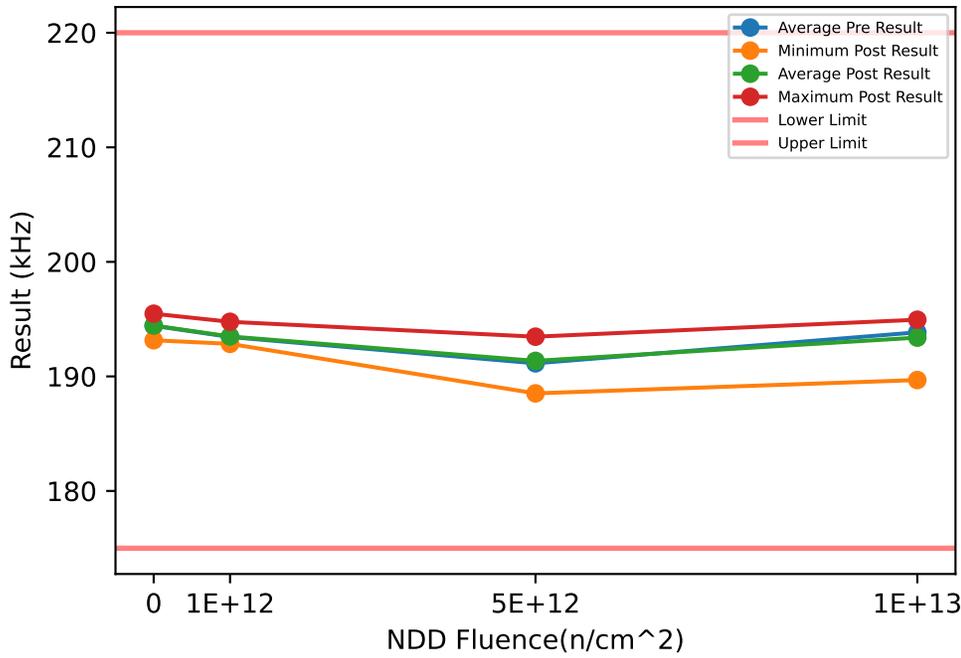
Device Test: 20.101 LEVEL|FREQ/RT/8/8/0/0/5/200kHz//@FSW_EXT_RT_B

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 175.0, Upper Limit = 220.0 (kHz))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	192.92	193.06	0.1449
2	1e+12	NDD	194.63	194.77	0.1323
3	1e+12	NDD	193.42	193.28	-0.1399
4	1e+12	NDD	192.79	192.84	0.0494
5	5e+12	NDD	188.18	188.52	0.3374
6	5e+12	NDD	192.33	192.41	0.0837
7	5e+12	NDD	191.02	191.03	0.0109
8	5e+12	NDD	193.04	193.47	0.4258
9	1e+13	NDD	189.93	189.68	-0.248
10	1e+13	NDD	195.06	194.32	-0.738
11	1e+13	NDD	195.43	194.95	-0.4775
12	1e+13	NDD	194.98	194.6	-0.3823
91	0	CORRELATION	193.71	193.77	0.0634
92	0	CORRELATION	195.33	195.39	0.0605
93	0	CORRELATION	193.15	193.16	0.0053
94	0	CORRELATION	195.48	195.47	-0.0049
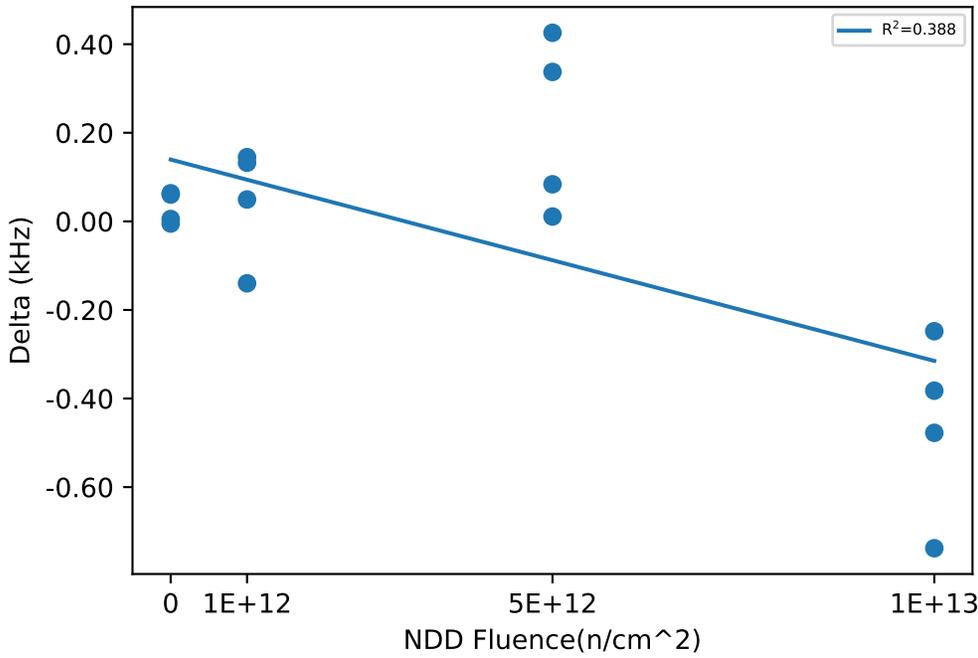
Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	193.15	194.42	195.48	1.1623	193.16	194.45	195.47	1.1624	-0.0049	0.031075	0.0634	0.035913
1e+12	192.79	193.44	194.63	0.84069	192.84	193.49	194.77	0.87124	-0.1399	0.046675	0.1449	0.1314
5e+12	188.18	191.14	193.04	2.1445	188.52	191.36	193.47	2.1394	0.0109	0.21445	0.4258	0.19859
1e+13	189.93	193.85	195.43	2.6185	189.68	193.39	194.95	2.4823	-0.738	-0.46145	-0.248	0.20701
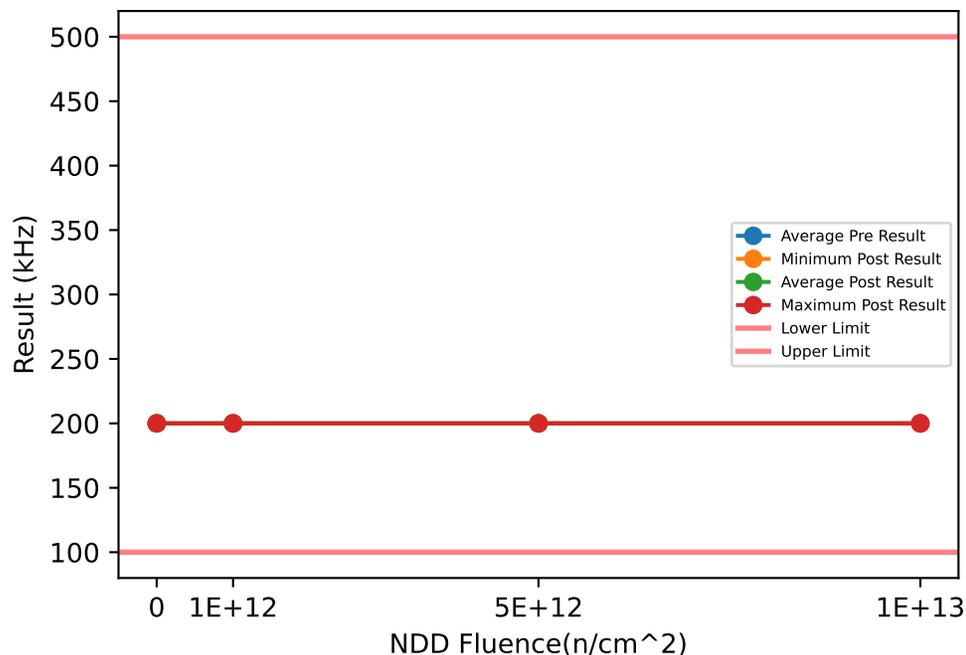
Device Test: 20.102 LEVEL|FREQ/SYNC/8/8/0/0/5/200kHz//@FREQ_SYNC_EXT_503X

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 100.0, Upper Limit = 500.0 (kHz))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	199.97	200	0.0301
2	1e+12	NDD	199.97	200	0.0324
3	1e+12	NDD	199.97	200	0.0323
4	1e+12	NDD	199.98	200	0.0219
5	5e+12	NDD	199.97	200	0.0273
6	5e+12	NDD	199.97	200	0.034
7	5e+12	NDD	199.97	200	0.0299
8	5e+12	NDD	199.98	200	0.0152
9	1e+13	NDD	199.99	200	0.0181
10	1e+13	NDD	199.97	200	0.023
11	1e+13	NDD	199.97	200	0.0261
12	1e+13	NDD	199.98	200	0.023
91	0	CORRELATION	199.99	200	0.0093
92	0	CORRELATION	199.98	200	0.0281
93	0	CORRELATION	199.97	200	0.0272
94	0	CORRELATION	199.98	200	0.0276
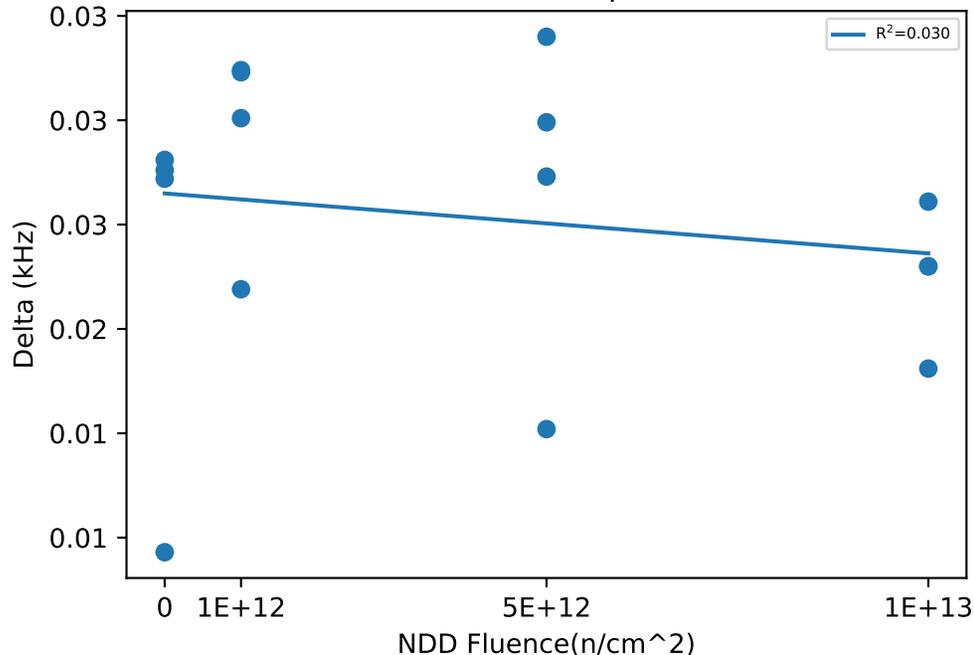
Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	199.97	199.98	199.99	0.0096521	200	200	200	0.0028371	0.0093	0.02305	0.0281	0.0091741
1e+12	199.97	199.97	199.98	0.0053867	200	200	200	0.00135	0.0219	0.029175	0.0324	0.0049648
5e+12	199.97	199.97	199.98	0.0062952	200	200	200	0.0036363	0.0152	0.0266	0.034	0.008085
1e+13	199.97	199.98	199.99	0.0070366	200	200	200	0.0037811	0.0181	0.02255	0.0261	0.0033071
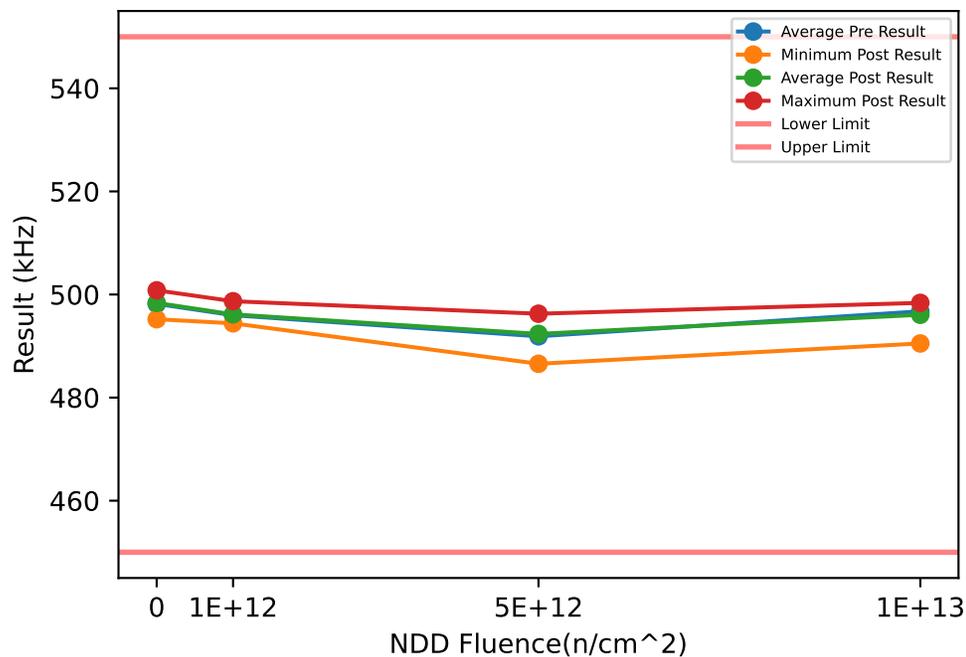
Device Test: 20.103 LEVEL|FREQ/RT/8/8/0/0/5/500kHz//@FSW_EXT_RT_C

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 450.0, Upper Limit = 550.0 (kHz))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	496.37	496.62	0.2562
2	1e+12	NDD	498.4	498.69	0.2945
3	1e+12	NDD	494.99	494.86	-0.1291
4	1e+12	NDD	494.15	494.41	0.2559
5	5e+12	NDD	486	486.56	0.5627
6	5e+12	NDD	493.86	494.12	0.2654
7	5e+12	NDD	492.15	492.49	0.331
8	5e+12	NDD	495.53	496.27	0.7394
9	1e+13	NDD	491.09	490.5	-0.5839
10	1e+13	NDD	498.35	497.37	-0.9805
11	1e+13	NDD	498.62	498.03	-0.5926
12	1e+13	NDD	498.91	498.37	-0.5405
91	0	CORRELATION	494.95	495.21	0.2582
92	0	CORRELATION	499.85	500.13	0.2817
93	0	CORRELATION	497.2	497.33	0.1318
94	0	CORRELATION	500.71	500.81	0.0927
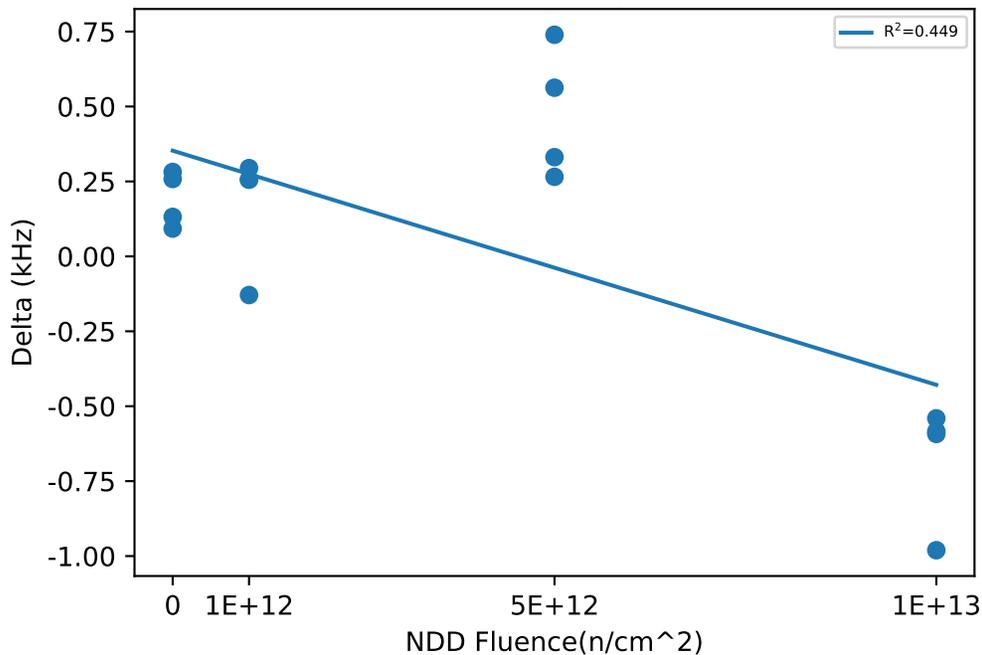
Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	494.95	498.18	500.71	2.6214	495.21	498.37	500.81	2.5902	0.0927	0.1911	0.2817	0.092933
1e+12	494.15	495.98	498.4	1.8548	494.41	496.15	498.69	1.9482	-0.1291	0.16937	0.2945	0.19981
5e+12	486	491.88	495.53	4.1602	486.56	492.36	496.27	4.1655	0.2654	0.47462	0.7394	0.21777
1e+13	491.09	496.74	498.91	3.7776	490.5	496.07	498.37	3.7335	-0.9805	-0.67437	-0.5405	0.20535

Device Test: 20.107 LEVEL|FREQ/RT/8/8/0/1000/5/100kHz//@FSW_EXT_RT_A

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 80.0, Upper Limit = 110.0 (kHz))

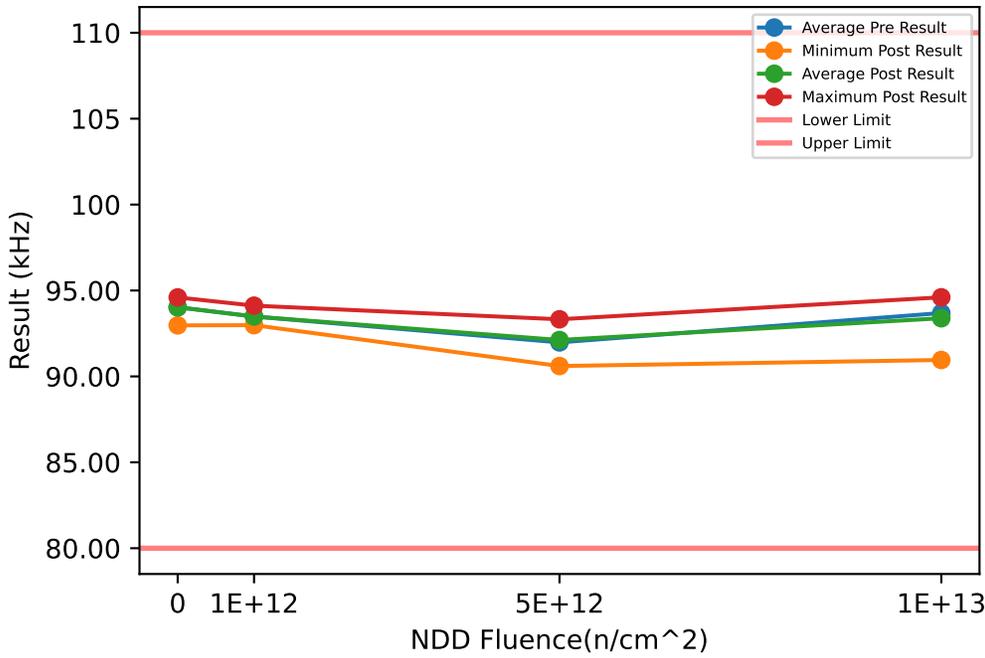| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	92.905	92.982	0.077
2	1e+12	NDD	94.084	94.117	0.0337
3	1e+12	NDD	93.722	93.624	-0.0978
4	1e+12	NDD	93.23	93.222	-0.0079
5	5e+12	NDD	90.361	90.604	0.243
6	5e+12	NDD	92.707	92.78	0.0729
7	5e+12	NDD	91.826	91.769	-0.0574
8	5e+12	NDD	93.022	93.324	0.3022
9	1e+13	NDD	91.079	90.956	-0.1231
10	1e+13	NDD	94.543	94.036	-0.5071
11	1e+13	NDD	94.91	94.604	-0.3066
12	1e+13	NDD	94.218	93.944	-0.2735
91	0	CORRELATION	93.975	93.984	0.0092
92	0	CORRELATION	94.524	94.534	0.0102
93	0	CORRELATION	93.012	92.971	-0.0411
94	0	CORRELATION	94.602	94.598	-0.0042
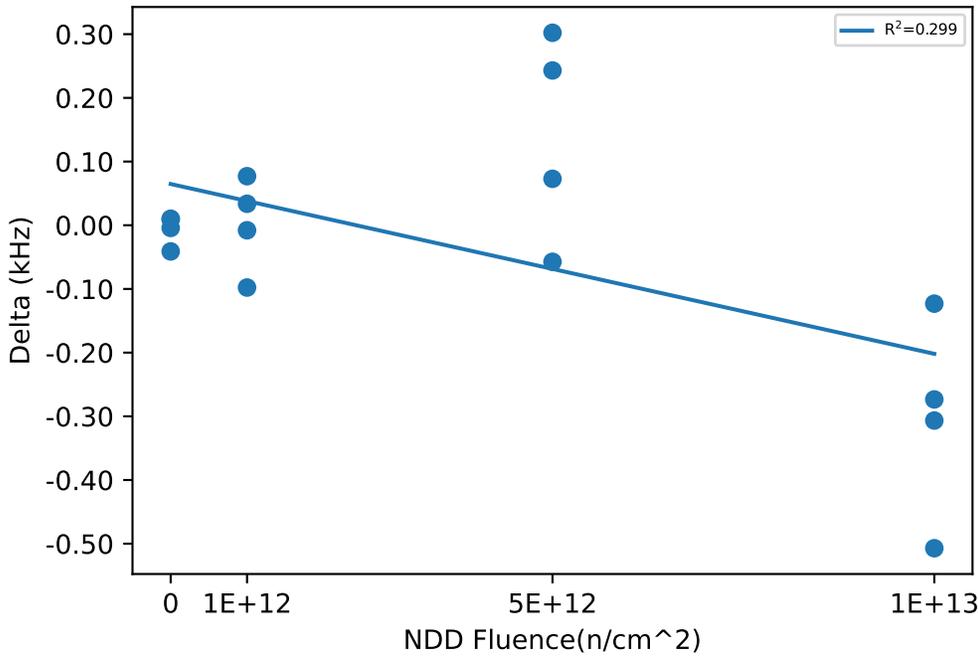
Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	93.012	94.028	94.602	0.73276	92.971	94.022	94.598	0.75285	-0.0411	-0.006475	0.0102	0.023999
1e+12	92.905	93.485	94.084	0.52144	92.982	93.486	94.117	0.49706	-0.0978	0.00125	0.077	0.074578
5e+12	90.361	91.979	93.022	1.1915	90.604	92.119	93.324	1.1982	-0.0574	0.14017	0.3022	0.16369
1e+13	91.079	93.688	94.91	1.7617	90.956	93.385	94.604	1.6453	-0.5071	-0.30258	-0.1231	0.15801
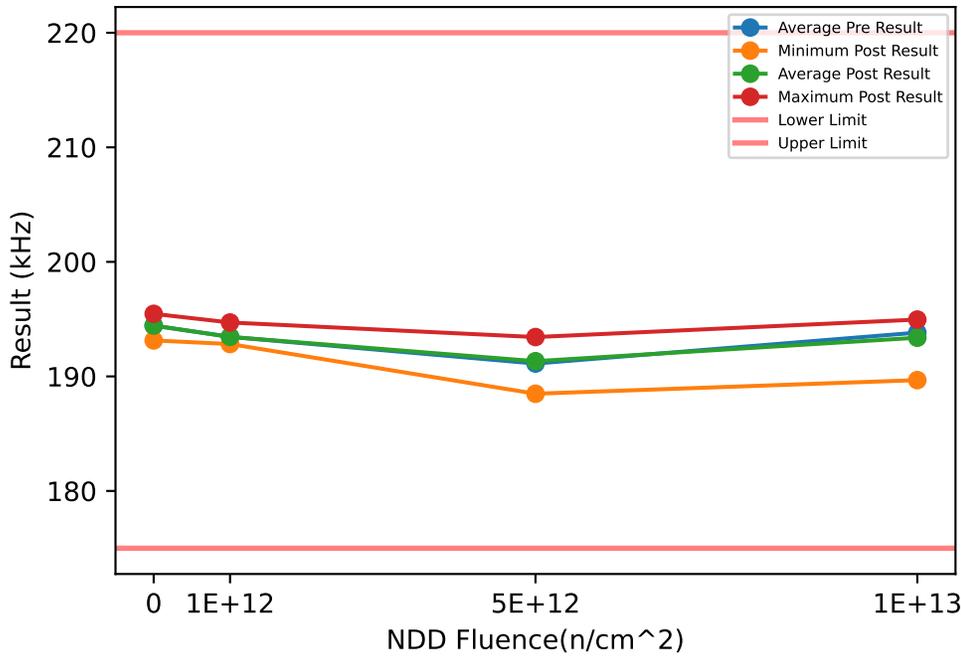
Device Test: 20.109 LEVEL|FREQ/RT/8/8/0/1000/5/200kHz//@FSW_EXT_RT_B

## NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 175.0, Upper Limit = 220.0 (kHz))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	192.93	193.01	0.0888
2	1e+12	NDD	194.65	194.71	0.0595
3	1e+12	NDD	193.43	193.26	-0.1764
4	1e+12	NDD	192.8	192.83	0.0236
5	5e+12	NDD	188.15	188.49	0.3341
6	5e+12	NDD	192.34	192.41	0.0745
7	5e+12	NDD	190.97	190.98	0.0112
8	5e+12	NDD	193.03	193.43	0.4028
9	1e+13	NDD	189.89	189.68	-0.2157
10	1e+13	NDD	195.04	194.32	-0.7181
11	1e+13	NDD	195.42	194.96	-0.4582
12	1e+13	NDD	194.95	194.56	-0.391
91	0	CORRELATION	193.74	193.79	0.0479
92	0	CORRELATION	195.33	195.36	0.0334
93	0	CORRELATION	193.18	193.14	-0.0379
94	0	CORRELATION	195.48	195.46	-0.0169
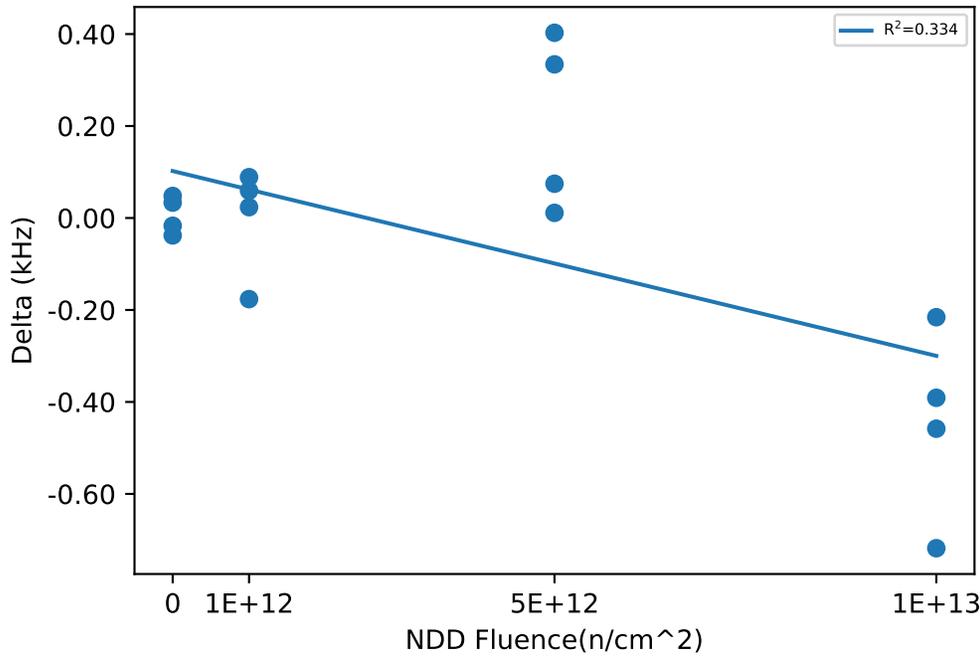
Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	193.18	194.43	195.48	1.1477	193.14	194.44	195.46	1.1561	-0.0379	0.006625	0.0479	0.040647
1e+12	192.8	193.45	194.65	0.84256	192.83	193.45	194.71	0.85584	-0.1764	-0.001125	0.0888	0.11985
5e+12	188.15	191.12	193.03	2.1574	188.49	191.33	193.43	2.1452	0.0112	0.20565	0.4028	0.19181
1e+13	189.89	193.82	195.42	2.629	189.68	193.38	194.96	2.4819	-0.7181	-0.44575	-0.2157	0.20837
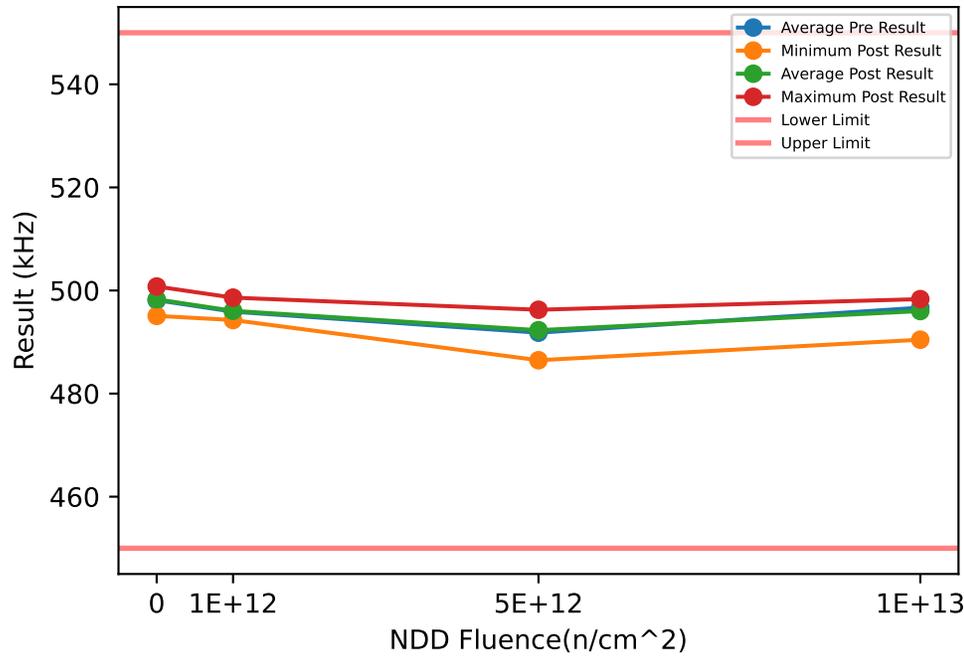
Device Test: 20.111 LEVEL|FREQ/RT/8/8/0/1000/5/500kHz//@FSW_EXT_RT_C

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 450.0, Upper Limit = 550.0 (kHz))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	496.26	496.54	0.2776
2	1e+12	NDD	498.27	498.61	0.3435
3	1e+12	NDD	494.93	494.8	-0.129
4	1e+12	NDD	494.09	494.27	0.1817
5	5e+12	NDD	485.88	486.47	0.591
6	5e+12	NDD	493.77	494.08	0.314
7	5e+12	NDD	492.13	492.39	0.2636
8	5e+12	NDD	495.48	496.26	0.7827
9	1e+13	NDD	491.02	490.45	-0.5687
10	1e+13	NDD	498.31	497.29	-1.0198
11	1e+13	NDD	498.56	497.97	-0.5896
12	1e+13	NDD	498.8	498.33	-0.4774
91	0	CORRELATION	494.87	495.07	0.2017
92	0	CORRELATION	499.83	500.04	0.206
93	0	CORRELATION	497.1	497.26	0.1593
94	0	CORRELATION	500.65	500.78	0.1235
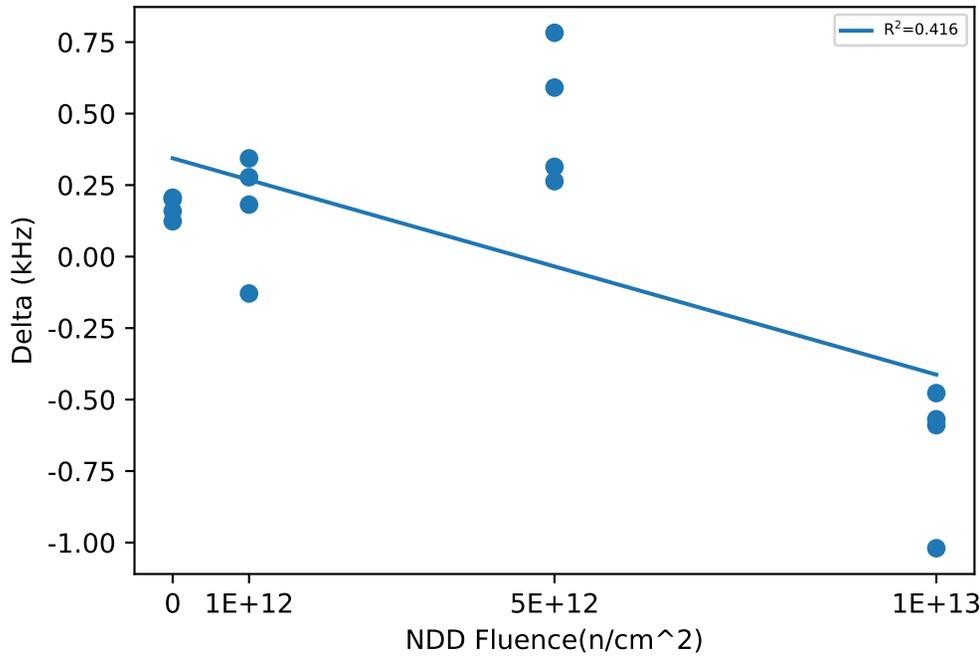
Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	494.87	498.11	500.65	2.6416	495.07	498.29	500.78	2.6232	0.1235	0.17262	0.206	0.038945
1e+12	494.09	495.89	498.27	1.8232	494.27	496.06	498.61	1.9615	-0.129	0.16845	0.3435	0.20913
5e+12	485.88	491.81	495.48	4.1868	486.47	492.3	496.26	4.1985	0.2636	0.48782	0.7827	0.24364
1e+13	491.02	496.67	498.8	3.7743	490.45	496.01	498.33	3.7303	-1.0198	-0.66388	-0.4774	0.24223

Device Test: 20.114 FREQ|DETECTION/SYNC/8/8/0/0/5/100kHz//@T_SYNC_DET

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 5.0 ((1/fsw) s))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	5	5	0
2	1e+12	NDD	5	5	0
3	1e+12	NDD	5	5	0
4	1e+12	NDD	5	5	0
5	5e+12	NDD	5	5	0
6	5e+12	NDD	5	5	0
7	5e+12	NDD	5	5	0
8	5e+12	NDD	5	5	0
9	1e+13	NDD	5	5	0
10	1e+13	NDD	5	5	0
11	1e+13	NDD	5	5	0
12	1e+13	NDD	5	5	0
91	0	CORRELATION	5	5	0
92	0	CORRELATION	5	5	0
93	0	CORRELATION	5	5	0
94	0	CORRELATION	5	5	0

Test Statistics ((1/fsw) s)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5	5	5	0	5	5	5	0	0	0	0	0
1e+12	5	5	5	0	5	5	5	0	0	0	0	0
5e+12	5	5	5	0	5	5	5	0	0	0	0	0
1e+13	5	5	5	0	5	5	5	0	0	0	0	0

Device Test: 20.116 FREQ|DETECTION/SYNC/8/8/0/0/5/200kHz//@T_SYNC_DET

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 5.0 ((1/fsw) s))

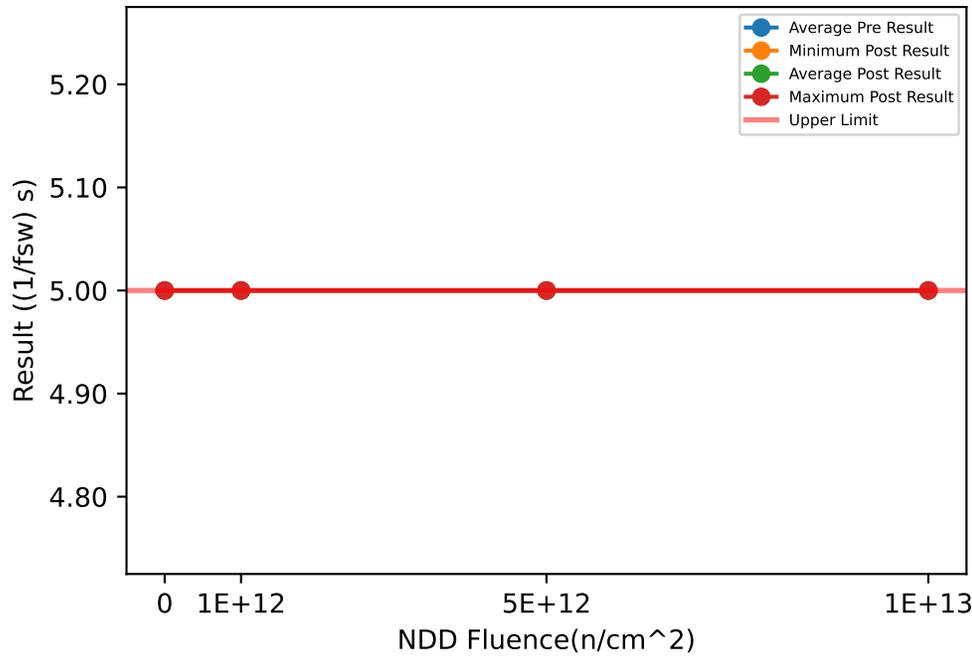| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	5	5	0
2	1e+12	NDD	5	5	0
3	1e+12	NDD	5	5	0
4	1e+12	NDD	5	5	0
5	5e+12	NDD	5	5	0
6	5e+12	NDD	5	5	0
7	5e+12	NDD	5	5	0
8	5e+12	NDD	5	5	0
9	1e+13	NDD	5	5	0
10	1e+13	NDD	5	5	0
11	1e+13	NDD	5	5	0
12	1e+13	NDD	5	5	0
91	0	CORRELATION	5	5	0
92	0	CORRELATION	5	5	0
93	0	CORRELATION	5	5	0
94	0	CORRELATION	5	5	0

Test Statistics ((1/fsw) s)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5	5	5	0	5	5	5	0	0	0	0	0
1e+12	5	5	5	0	5	5	5	0	0	0	0	0
5e+12	5	5	5	0	5	5	5	0	0	0	0	0
1e+13	5	5	5	0	5	5	5	0	0	0	0	0

Device Test: 20.118 FREQ|DETECTION/SYNC/8/8/0/0/5/500kHz//@T_SYNC_DET

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 5.0 ((1/fsw) s))

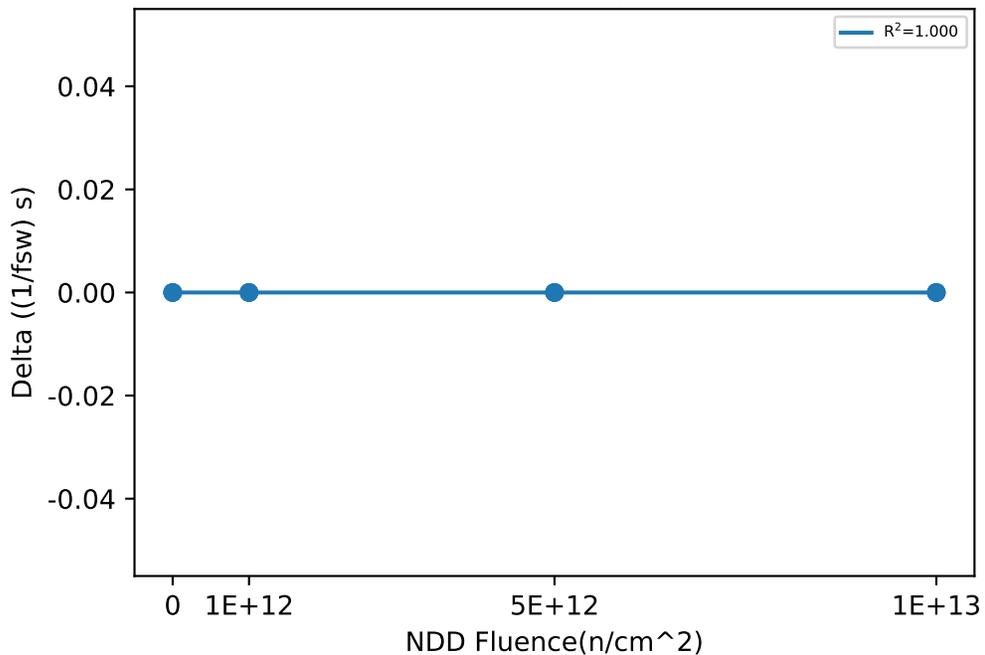| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	5	5	0
2	1e+12	NDD	5	5	0
3	1e+12	NDD	5	5	0
4	1e+12	NDD	5	5	0
5	5e+12	NDD	5	5	0
6	5e+12	NDD	5	5	0
7	5e+12	NDD	5	5	0
8	5e+12	NDD	5	5	0
9	1e+13	NDD	5	5	0
10	1e+13	NDD	5	5	0
11	1e+13	NDD	5	5	0
12	1e+13	NDD	5	5	0
91	0	CORRELATION	5	5	0
92	0	CORRELATION	5	5	0
93	0	CORRELATION	5	5	0
94	0	CORRELATION	5	5	0

Test Statistics ((1/fsw) s)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5	5	5	0	5	5	5	0	0	0	0	0
1e+12	5	5	5	0	5	5	5	0	0	0	0	0
5e+12	5	5	5	0	5	5	5	0	0	0	0	0
1e+13	5	5	5	0	5	5	5	0	0	0	0	0

Device Test: 20.120 FREQ|DETECTION/RT/8/8/0/0/5/100kHz//@T_INT_CLK_DET

NDD vs Result Stats

Legend:
- Average Pre Result
- Minimum Post Result
- Average Post Result
- Maximum Post Result
- Upper Limit

NDD vs Post - Pre Exposure Delta

$R^2=0.012$

Test Results (Upper Limit = 5.0 ((1/fsw) s))

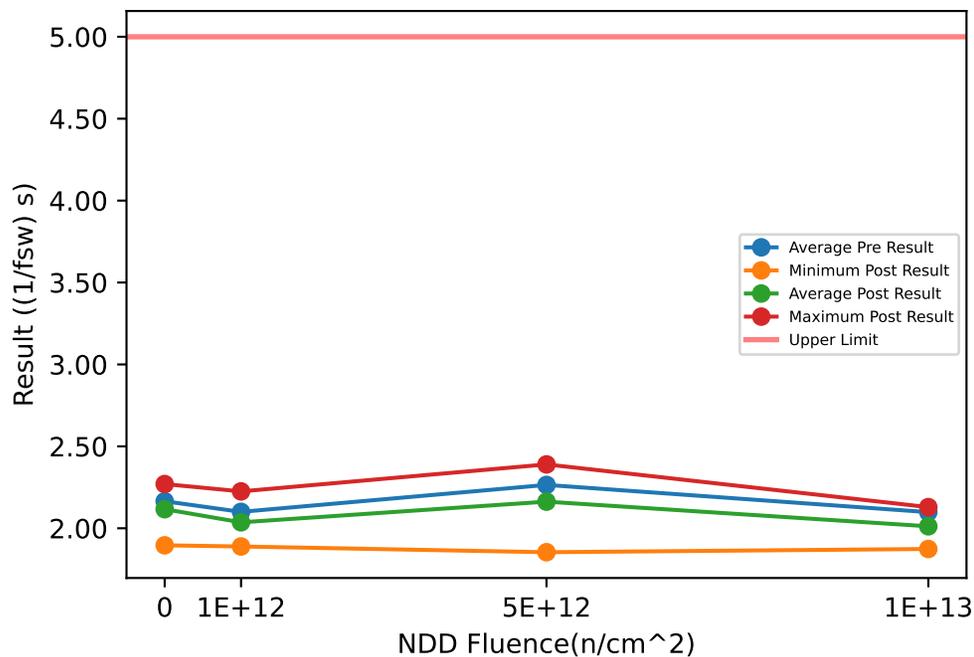| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	2.4808	2.0328	-0.448
2	1e+12	NDD	1.8833	1.8889	0.0056
3	1e+12	NDD	2.1066	2.2251	0.1185
4	1e+12	NDD	1.9299	1.9983	0.0684
5	5e+12	NDD	2.5056	2.3382	-0.1674
6	5e+12	NDD	2.1104	1.8538	-0.2566
7	5e+12	NDD	2.4164	2.3898	-0.0266
8	5e+12	NDD	2.0262	2.0682	0.042
9	1e+13	NDD	2.3614	2.1291	-0.2323
10	1e+13	NDD	1.9741	1.9792	0.0051
11	1e+13	NDD	2.0971	2.0662	-0.0309
12	1e+13	NDD	1.9613	1.8737	-0.0876
91	0	CORRELATION	2.3078	2.2698	-0.038
92	0	CORRELATION	2.002	1.896	-0.106
93	0	CORRELATION	2.2366	2.223	-0.0136
94	0	CORRELATION	2.113	2.0774	-0.0356
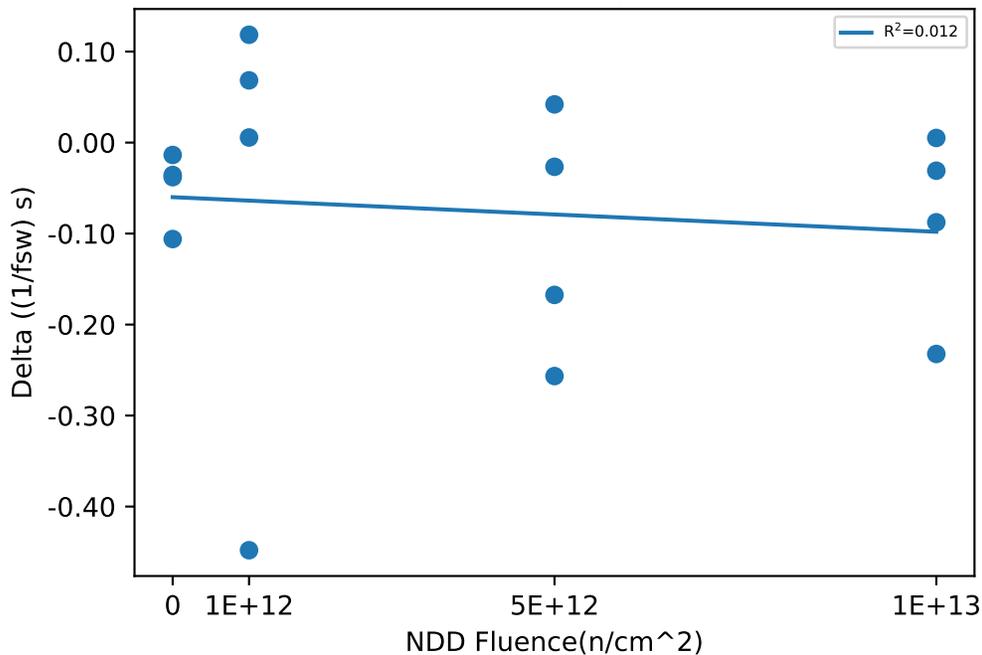
Test Statistics ((1/fsw) s)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.002	2.1648	2.3078	0.13514	1.896	2.1166	2.2698	0.16832	-0.106	-0.0483	-0.0136	0.040003
1e+12	1.8833	2.1002	2.4808	0.27138	1.8889	2.0363	2.2251	0.14003	-0.448	-0.063875	0.1185	0.26022
5e+12	2.0262	2.2646	2.5056	0.23219	1.8538	2.1625	2.3898	0.24948	-0.2566	-0.10215	0.042	0.13491
1e+13	1.9613	2.0985	2.3614	0.18567	1.8737	2.012	2.1291	0.11083	-0.2323	-0.086425	0.0051	0.10447

Device Test: 20.122 FREQ|DETECTION/RT/8/8/0/0/5/200kHz//@T_INT_CLK_DET

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 5.0 ((1/fsw) s))

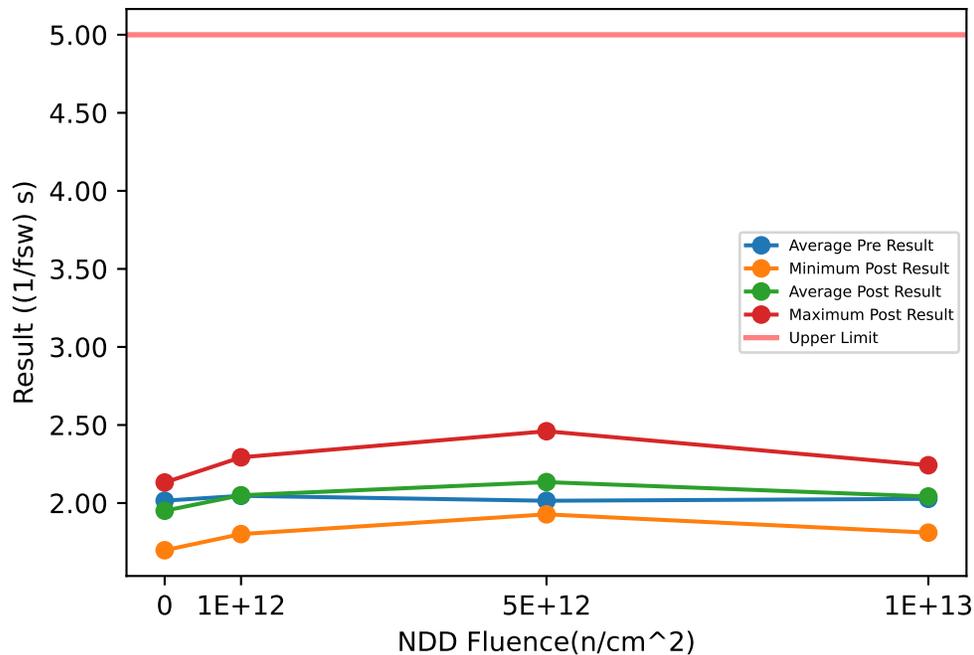| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	2.251	2.2323	-0.0187
2	1e+12	NDD	1.7662	1.8732	0.107
3	1e+12	NDD	2.1838	2.2929	0.1091
4	1e+12	NDD	1.984	1.8012	-0.1828
5	5e+12	NDD	2.3519	2.192	-0.1599
6	5e+12	NDD	1.7779	1.9277	0.1498
7	5e+12	NDD	1.9783	2.4601	0.4818
8	5e+12	NDD	1.9505	1.957	0.0065
9	1e+13	NDD	2.276	2.2423	-0.0337
10	1e+13	NDD	1.9483	1.8103	-0.138
11	1e+13	NDD	2.0035	2.2121	0.2086
12	1e+13	NDD	1.879	1.9034	0.0244
91	0	CORRELATION	2.2494	2.0169	-0.2325
92	0	CORRELATION	1.8412	1.9566	0.1154
93	0	CORRELATION	2.2201	2.1316	-0.0885
94	0	CORRELATION	1.7499	1.6978	-0.0521
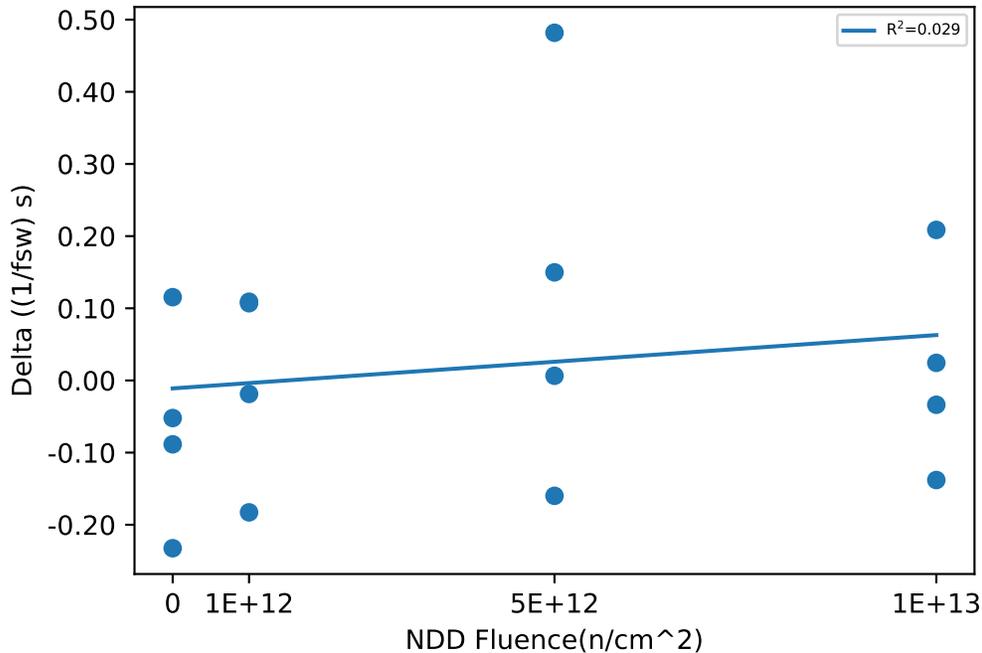
Test Statistics ((1/fsw) s)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.7499	2.0151	2.2494	0.25658	1.6978	1.9507	2.1316	0.18358	-0.2325	-0.064425	0.1154	0.14297
1e+12	1.7662	2.0463	2.251	0.21844	1.8012	2.0499	2.2929	0.24859	-0.1828	0.00365	0.1091	0.13792
5e+12	1.7779	2.0147	2.3519	0.24168	1.9277	2.1342	2.4601	0.24738	-0.1599	0.11955	0.4818	0.27265
1e+13	1.879	2.0267	2.276	0.17383	1.8103	2.042	2.2423	0.21752	-0.138	0.015325	0.2086	0.14532

Device Test: 20.124 FREQ|DETECTION/RT/8/8/0/0/5/500kHz//@T_INT_CLK_DET

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 5.0 ((1/fsw) s))

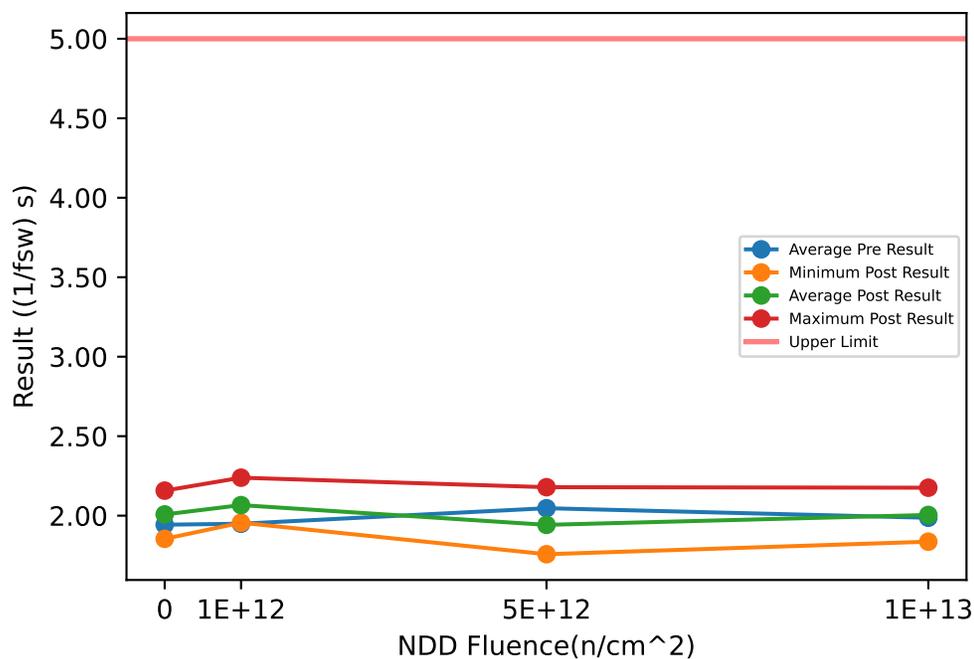| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	2.0239	2.0409	0.017
2	1e+12	NDD	1.8963	1.9557	0.0594
3	1e+12	NDD	2	2.2388	0.2388
4	1e+12	NDD	1.8763	2.0298	0.1535
5	5e+12	NDD	2.1954	1.9627	-0.2327
6	5e+12	NDD	1.7857	1.8693	0.0836
7	5e+12	NDD	2.2897	2.1791	-0.1106
8	5e+12	NDD	1.9165	1.7574	-0.1591
9	1e+13	NDD	2.1703	2.1758	0.0055
10	1e+13	NDD	1.825	1.9407	0.1157
11	1e+13	NDD	2.1603	2.0647	-0.0956
12	1e+13	NDD	1.7912	1.8363	0.0451
91	0	CORRELATION	2.0004	2.0919	0.0915
92	0	CORRELATION	1.9168	1.8541	-0.0627
93	0	CORRELATION	2.1453	2.1574	0.0121
94	0	CORRELATION	1.7101	1.9272	0.2171
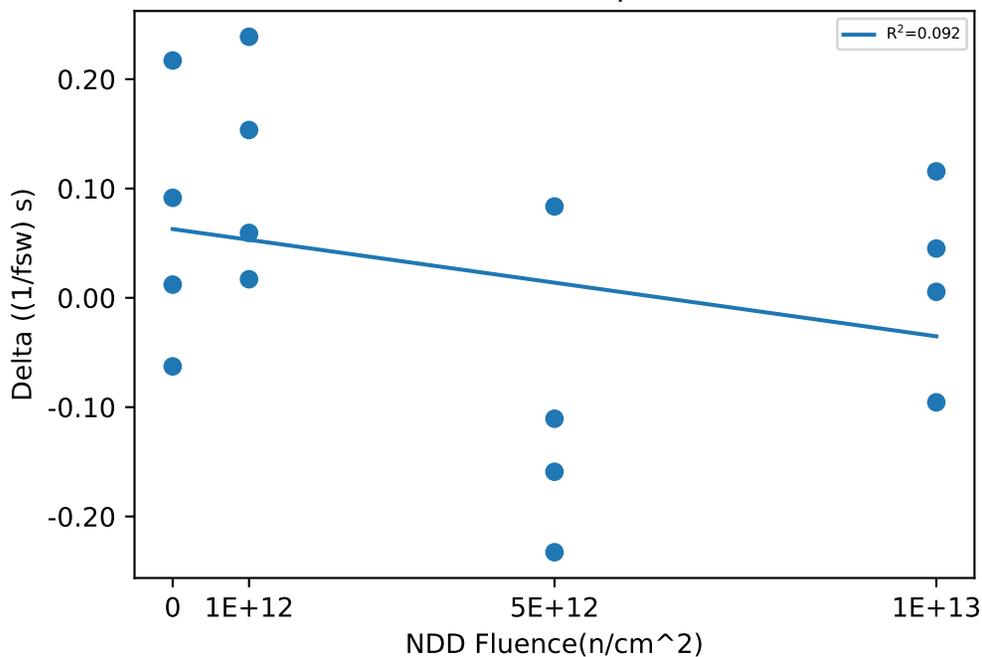
Test Statistics ((1/fsw) s)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.7101	1.9431	2.1453	0.1818	1.8541	2.0076	2.1574	0.14092	-0.0627	0.0645	0.2171	0.11964
1e+12	1.8763	1.9491	2.0239	0.073651	1.9557	2.0663	2.2388	0.12106	0.017	0.11717	0.2388	0.099138
5e+12	1.7857	2.0468	2.2897	0.2354	1.7574	1.9421	2.1791	0.17889	-0.2327	-0.1047	0.0836	0.1352
1e+13	1.7912	1.9867	2.1703	0.20673	1.8363	2.0044	2.1758	0.14757	-0.0956	0.017675	0.1157	0.088205
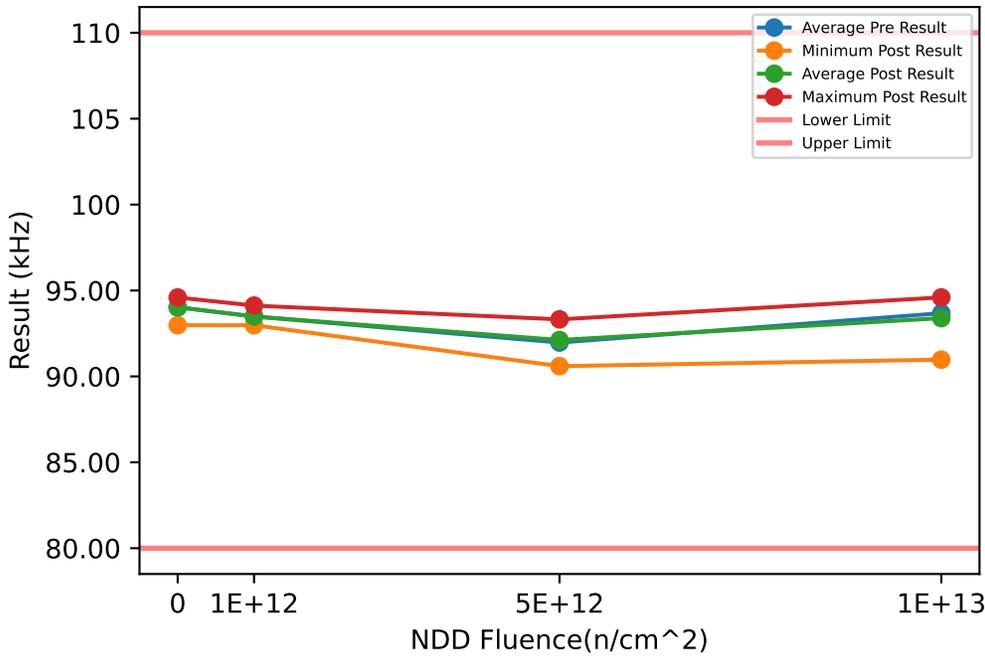
Device Test: 20.27 LEVEL|FREQ/RT/12/12/0/0/5/100kHz//@FSW_EXT_RT_A

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 80.0, Upper Limit = 110.0 (kHz))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	92.916	92.978	0.062
2	1e+12	NDD	94.091	94.121	0.0296
3	1e+12	NDD	93.733	93.623	-0.1098
4	1e+12	NDD	93.219	93.226	0.0072
5	5e+12	NDD	90.341	90.596	0.2547
6	5e+12	NDD	92.711	92.781	0.0699
7	5e+12	NDD	91.814	91.776	-0.0377
8	5e+12	NDD	93.013	93.319	0.3057
9	1e+13	NDD	91.072	90.976	-0.0963
10	1e+13	NDD	94.534	94.036	-0.4976
11	1e+13	NDD	94.906	94.597	-0.309
12	1e+13	NDD	94.207	93.951	-0.2555
91	0	CORRELATION	93.973	93.986	0.0132
92	0	CORRELATION	94.515	94.537	0.0226
93	0	CORRELATION	93.004	92.979	-0.0243
94	0	CORRELATION	94.591	94.595	0.0035
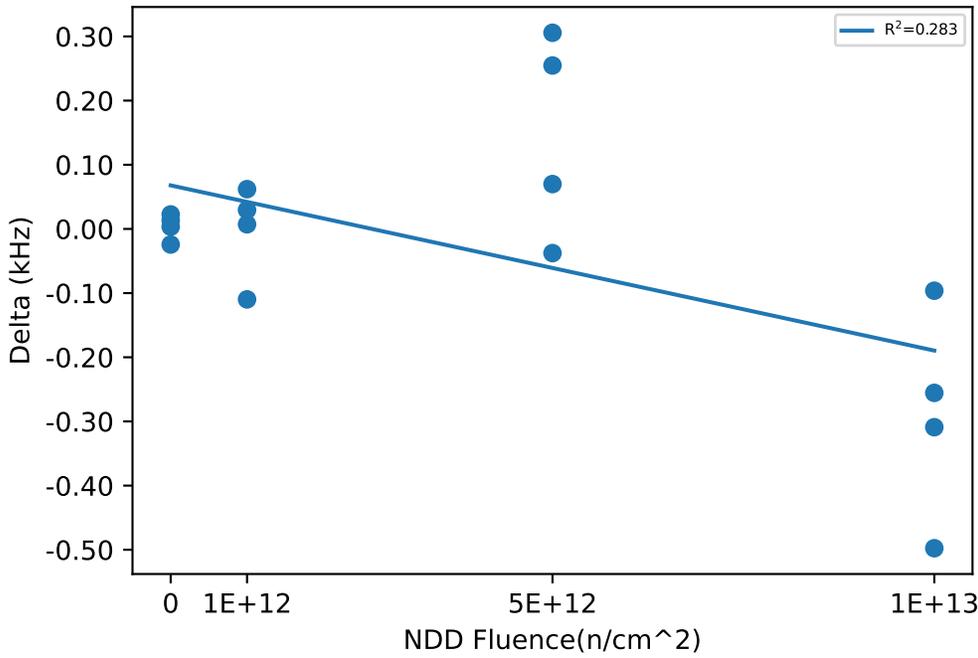
Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	93.004	94.021	94.591	0.73179	92.979	94.024	94.595	0.74884	-0.0243	0.00375	0.0226	0.020261
1e+12	92.916	93.49	94.091	0.52383	92.978	93.487	94.121	0.49906	-0.1098	-0.00275	0.062	0.074828
5e+12	90.341	91.97	93.013	1.1994	90.596	92.118	93.319	1.1995	-0.0377	0.14815	0.3057	0.16004
1e+13	91.072	93.68	94.906	1.7615	90.976	93.39	94.597	1.6346	-0.4976	-0.2896	-0.0963	0.1655
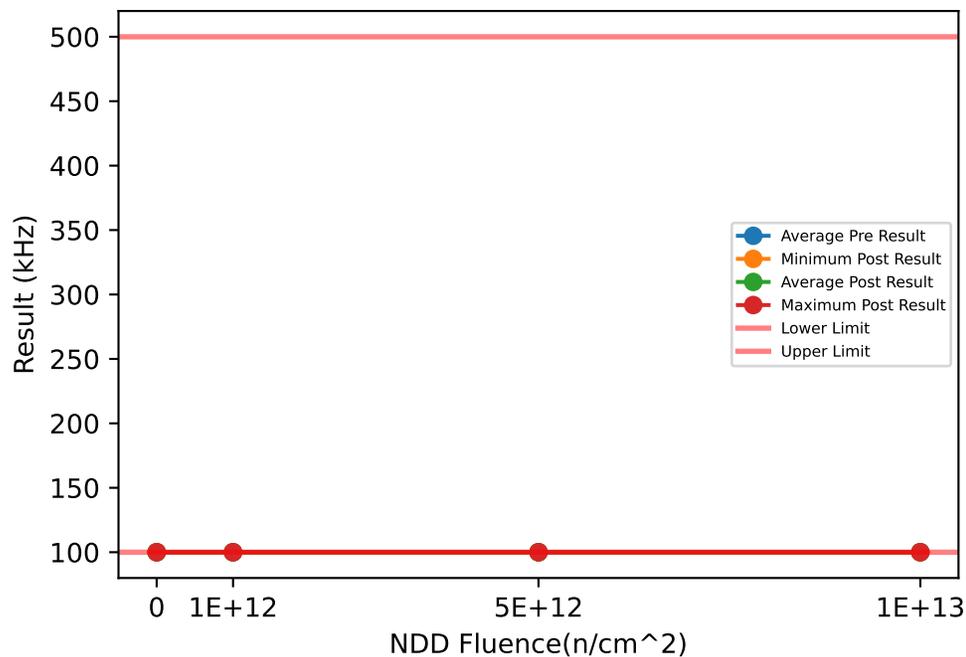
Device Test: 20.28 LEVEL|FREQ/SYNC/12/12/0/0/5/100kHz//@FREQ_SYNC_EXT_503X

## NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 100.0, Upper Limit = 500.0 (kHz))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	99.996	99.999	0.0023
2	1e+12	NDD	99.994	100	0.0059
3	1e+12	NDD	99.992	99.999	0.0069
4	1e+12	NDD	99.994	100	0.0064
5	5e+12	NDD	99.994	99.999	0.0045
6	5e+12	NDD	99.995	100	0.005
7	5e+12	NDD	99.993	100	0.0075
8	5e+12	NDD	99.994	100	0.0069
9	1e+13	NDD	99.998	100	0.0018
10	1e+13	NDD	99.994	100	0.0077
11	1e+13	NDD	99.994	99.999	0.0054
12	1e+13	NDD	99.996	100	0.0053
91	0	CORRELATION	99.995	100	0.0061
92	0	CORRELATION	99.993	100	0.0068
93	0	CORRELATION	99.993	100	0.0067
94	0	CORRELATION	99.995	100	0.0046
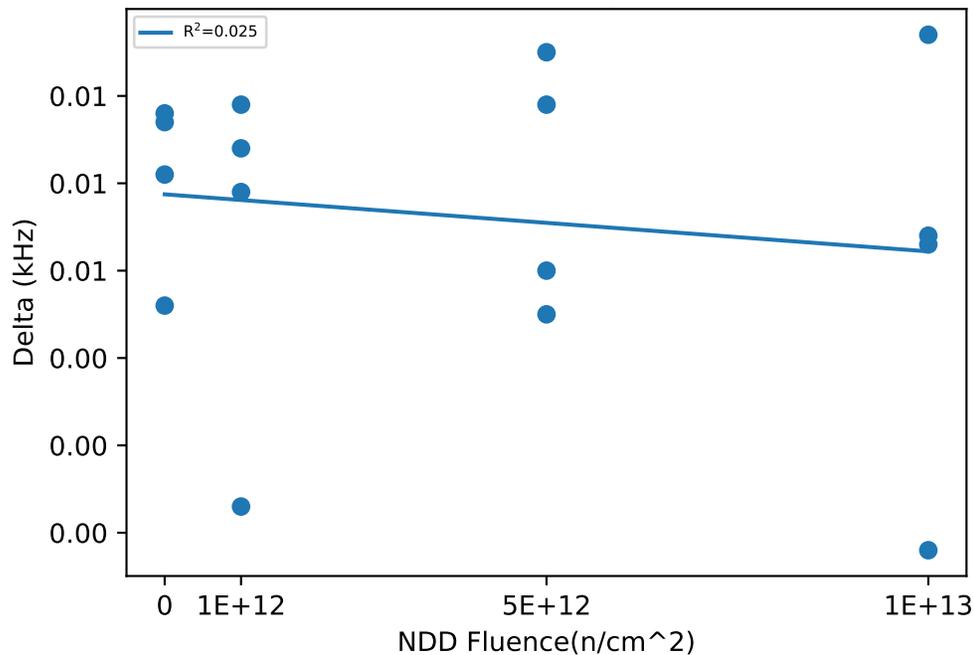
Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	99.993	99.994	99.995	0.0010275	100	100	100	0.0003594	0.0046	0.00605	0.0068	0.0010149
1e+12	99.992	99.994	99.996	0.0018129	99.999	99.999	100	0.00072744	0.0023	0.005375	0.0069	0.0020903
5e+12	99.993	99.994	99.995	0.00057373	99.999	100	100	0.00096782	0.0045	0.005975	0.0075	0.00145
1e+13	99.994	99.995	99.998	0.0019149	99.999	100	100	0.001121	0.0018	0.00505	0.0077	0.0024338

Device Test: 20.29 PF|DCL_40/SYNC/12/12/0/0/5/100kHz//@DUTY_SYNC_EXT

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 40.0, Upper Limit = 60.0 (%))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	40	40	0
2	1e+12	NDD	40	40	0
3	1e+12	NDD	40	40	0
4	1e+12	NDD	40	40	0
5	5e+12	NDD	40	40	0
6	5e+12	NDD	40	40	0
7	5e+12	NDD	40	40	0
8	5e+12	NDD	40	40	0
9	1e+13	NDD	40	40	0
10	1e+13	NDD	40	40	0
11	1e+13	NDD	40	40	0
12	1e+13	NDD	40	40	0
91	0	CORRELATION	40	40	0
92	0	CORRELATION	40	40	0
93	0	CORRELATION	40	40	0
94	0	CORRELATION	40	40	0

Test Statistics (%)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	40	40	40	0	40	40	40	0	0	0	0	0
1e+12	40	40	40	0	40	40	40	0	0	0	0	0
5e+12	40	40	40	0	40	40	40	0	0	0	0	0
1e+13	40	40	40	0	40	40	40	0	0	0	0	0

Device Test: 20.30 PF|DCL_60/SYNC/12/12/0/0/5/100kHz//@DUTY_SYNC_EXT

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 40.0, Upper Limit = 60.0 (%))

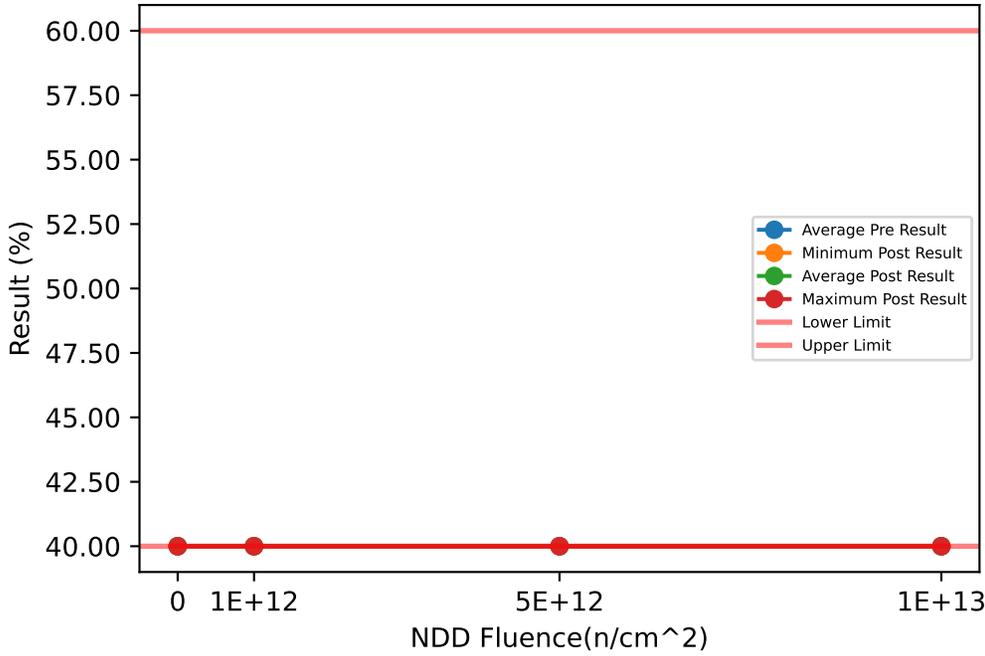| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	60	60	0
2	1e+12	NDD	60	60	0
3	1e+12	NDD	60	60	0
4	1e+12	NDD	60	60	0
5	5e+12	NDD	60	60	0
6	5e+12	NDD	60	60	0
7	5e+12	NDD	60	60	0
8	5e+12	NDD	60	60	0
9	1e+13	NDD	60	60	0
10	1e+13	NDD	60	60	0
11	1e+13	NDD	60	60	0
12	1e+13	NDD	60	60	0
91	0	CORRELATION	60	60	0
92	0	CORRELATION	60	60	0
93	0	CORRELATION	60	60	0
94	0	CORRELATION	60	60	0

Test Statistics (%)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	60	60	60	0	60	60	60	0	0	0	0	0
1e+12	60	60	60	0	60	60	60	0	0	0	0	0
5e+12	60	60	60	0	60	60	60	0	0	0	0	0
1e+13	60	60	60	0	60	60	60	0	0	0	0	0

Device Test: 20.31 LEVEL|FREQ/RT/14/14/0/0/5/100kHz//@FSW_EXT_RT_A

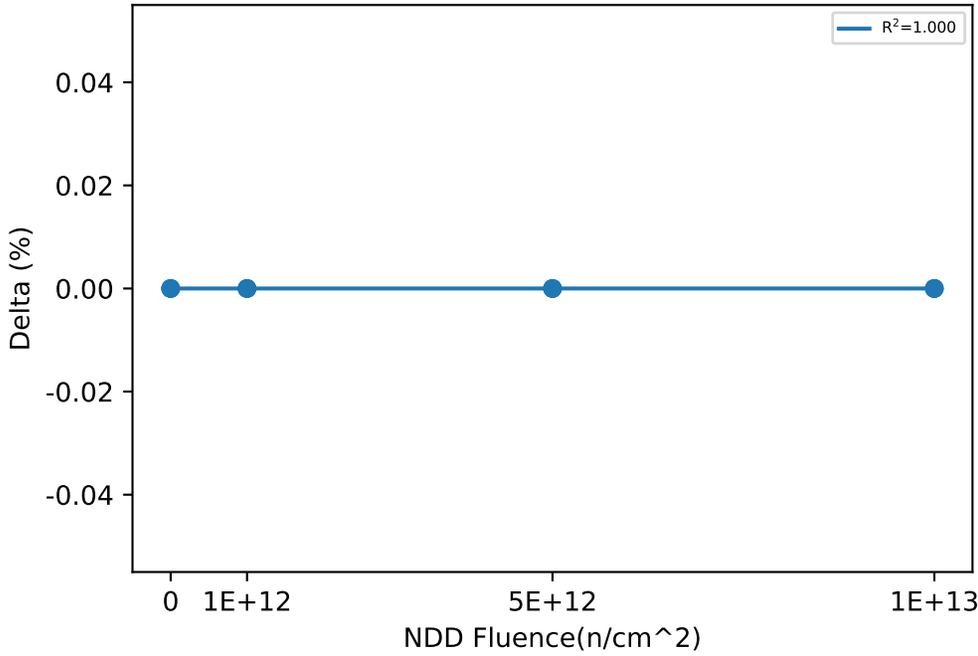## NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 80.0, Upper Limit = 110.0 (kHz))

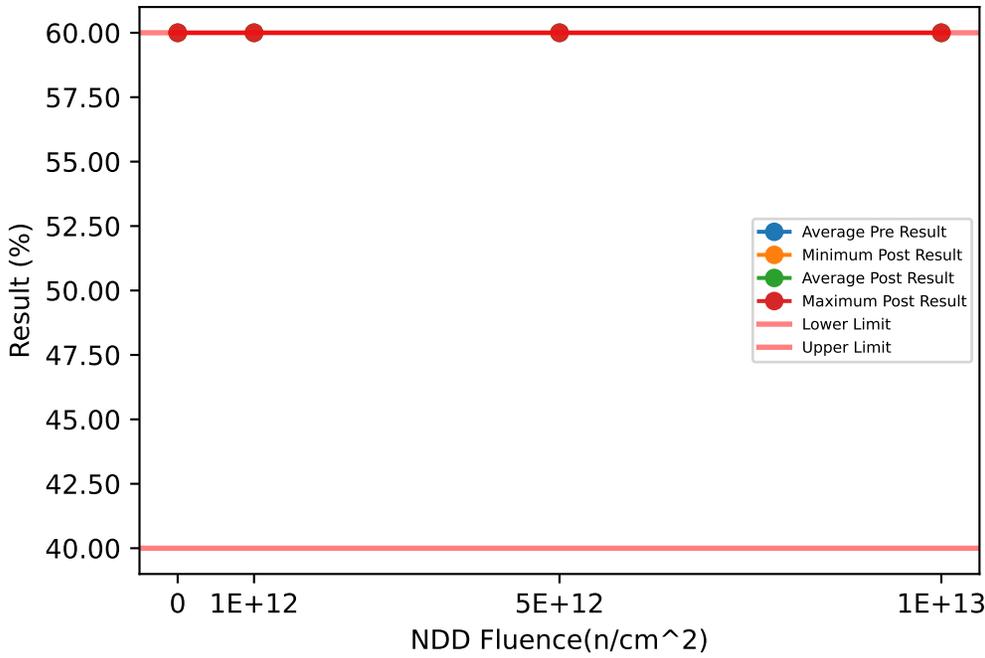| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	92.906	92.959	0.0537
2	1e+12	NDD	94.087	94.12	0.0337
3	1e+12	NDD	93.717	93.61	-0.107
4	1e+12	NDD	93.214	93.218	0.0033
5	5e+12	NDD	90.342	90.584	0.2417
6	5e+12	NDD	92.715	92.785	0.0703
7	5e+12	NDD	91.802	91.766	-0.0357
8	5e+12	NDD	93.022	93.311	0.2889
9	1e+13	NDD	91.07	90.955	-0.1155
10	1e+13	NDD	94.538	94.038	-0.4993
11	1e+13	NDD	94.906	94.584	-0.3213
12	1e+13	NDD	94.218	93.943	-0.2749
91	0	CORRELATION	93.957	93.957	-0.0005
92	0	CORRELATION	94.522	94.539	0.0164
93	0	CORRELATION	93.007	92.973	-0.0335
94	0	CORRELATION	94.587	94.591	0.0037

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	93.007	94.018	94.587	0.73139	92.973	94.015	94.591	0.75161	-0.0335	-0.003475	0.0164	0.021267
1e+12	92.906	93.481	94.087	0.52443	92.959	93.477	94.12	0.50569	-0.107	-0.004075	0.0537	0.071677
5e+12	90.342	91.97	93.022	1.2027	90.584	92.111	93.311	1.2035	-0.0357	0.1413	0.2889	0.15082
1e+13	91.07	93.683	94.906	1.7643	90.955	93.38	94.584	1.6415	-0.4993	-0.30275	-0.1155	0.15792

Device Test: 20.32 LEVEL|FREQ/SYNC/14/14/0/0/5/100kHz//@FREQ_SYNC_EXT_503X

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 100.0, Upper Limit = 500.0 (kHz))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	99.997	100	0.0029
2	1e+12	NDD	99.994	100	0.0078
3	1e+12	NDD	99.992	99.999	0.0073
4	1e+12	NDD	99.994	100	0.0069
5	5e+12	NDD	99.996	99.966	-0.0296
6	5e+12	NDD	99.993	100	0.0095
7	5e+12	NDD	99.993	100	0.0074
8	5e+12	NDD	99.994	99.999	0.0055
9	1e+13	NDD	99.996	100	0.0044
10	1e+13	NDD	99.995	99.999	0.0039
11	1e+13	NDD	99.991	100	0.0083
12	1e+13	NDD	99.995	99.999	0.0038
91	0	CORRELATION	99.998	100	0.0019
92	0	CORRELATION	99.995	100	0.0062
93	0	CORRELATION	99.993	99.999	0.0064
94	0	CORRELATION	99.996	100	0.0048

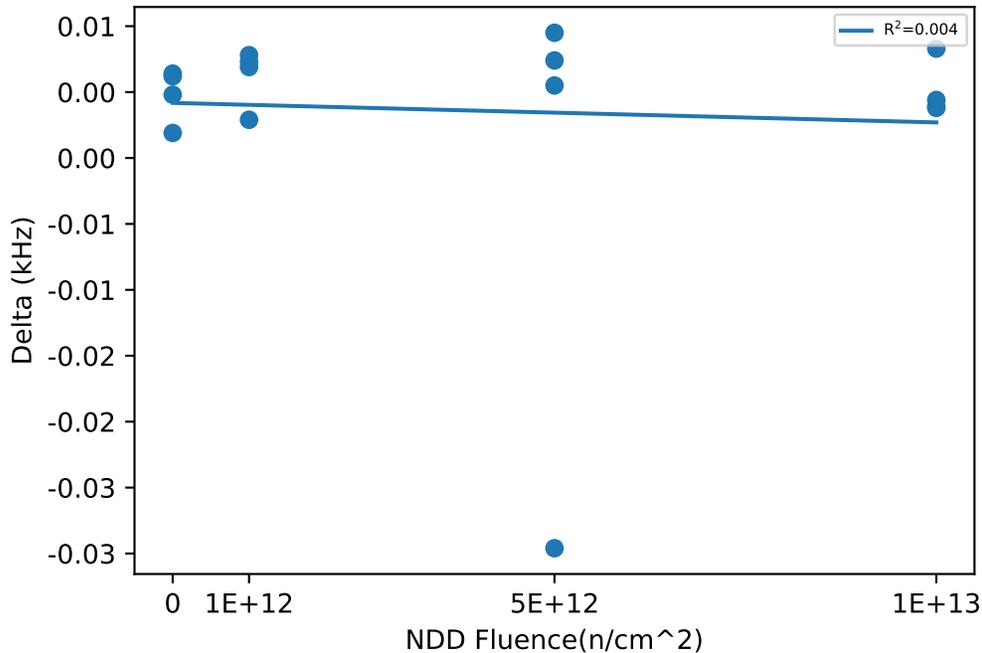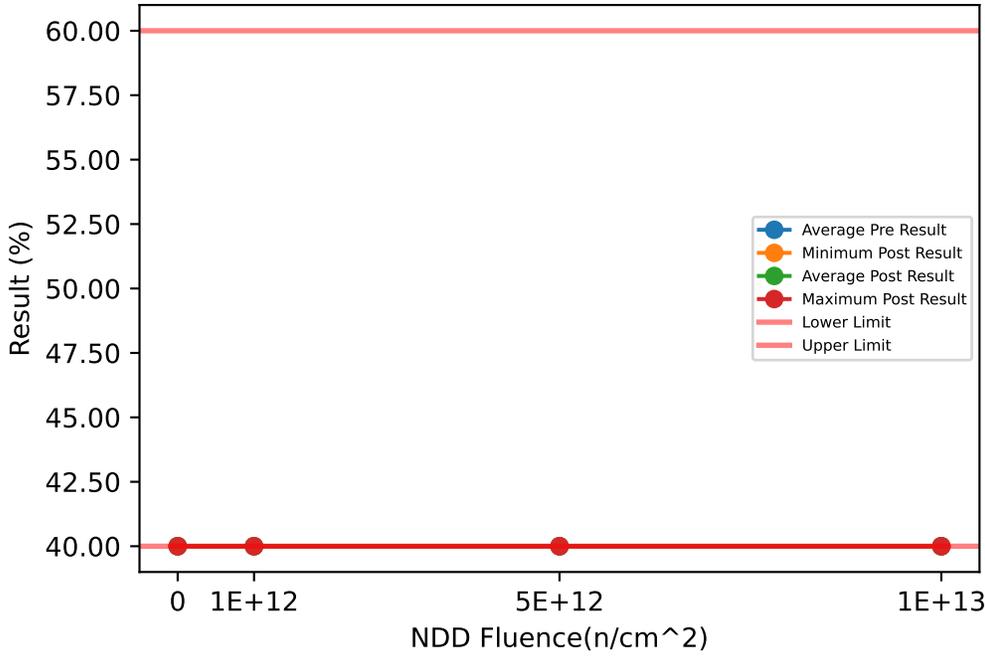## Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	99.993	99.996	99.998	0.0023056	99.999	100	100	0.0010165	0.0019	0.004825	0.0064	0.0020759
1e+12	99.992	99.994	99.997	0.0021747	99.999	100	100	0.0011776	0.0029	0.006225	0.0078	0.002247
5e+12	99.993	99.994	99.996	0.0014385	99.966	99.992	100	0.017249	-0.0296	-0.0018	0.0095	0.018605
1e+13	99.991	99.994	99.996	0.0020347	99.999	99.999	100	0.00059442	0.0038	0.0051	0.0083	0.0021494

Device Test: 20.33 PF|DCL_40/SYNC/14/14/0/0/5/100kHz//@DUTY_SYNC_EXT

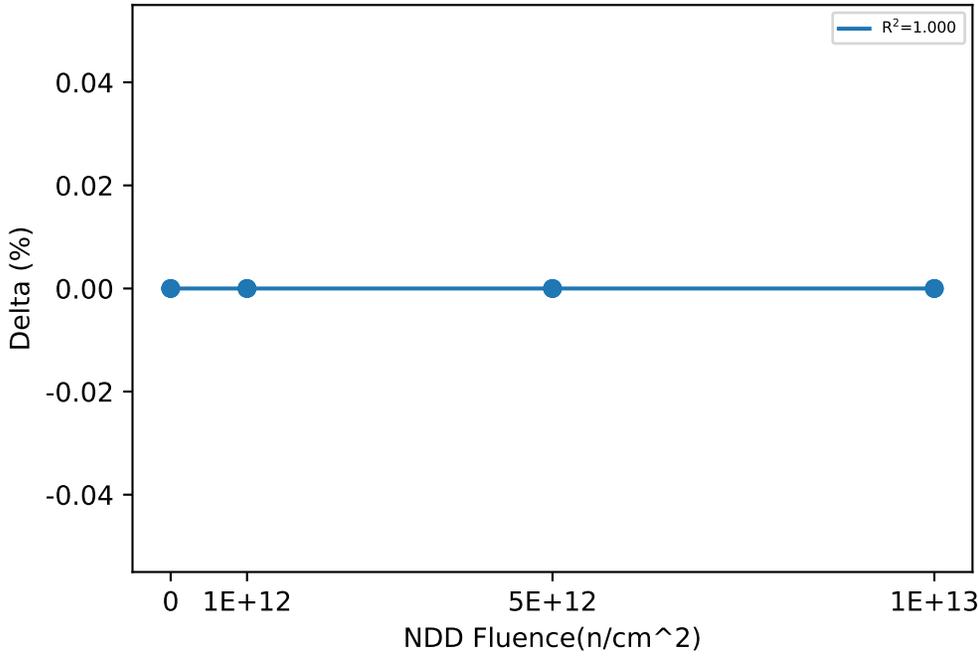## NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 40.0, Upper Limit = 60.0 (%))

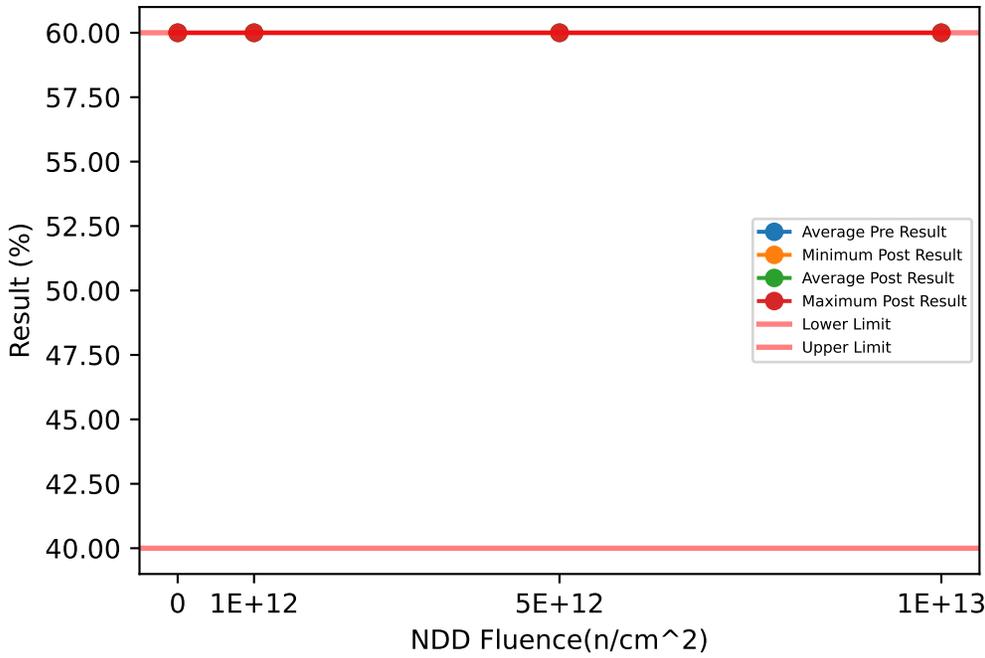| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	40	40	0
2	1e+12	NDD	40	40	0
3	1e+12	NDD	40	40	0
4	1e+12	NDD	40	40	0
5	5e+12	NDD	40	40	0
6	5e+12	NDD	40	40	0
7	5e+12	NDD	40	40	0
8	5e+12	NDD	40	40	0
9	1e+13	NDD	40	40	0
10	1e+13	NDD	40	40	0
11	1e+13	NDD	40	40	0
12	1e+13	NDD	40	40	0
91	0	CORRELATION	40	40	0
92	0	CORRELATION	40	40	0
93	0	CORRELATION	40	40	0
94	0	CORRELATION	40	40	0

Test Statistics (%)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	40	40	40	0	40	40	40	0	0	0	0	0
1e+12	40	40	40	0	40	40	40	0	0	0	0	0
5e+12	40	40	40	0	40	40	40	0	0	0	0	0
1e+13	40	40	40	0	40	40	40	0	0	0	0	0

Device Test: 20.34 PF|DCL_60/SYNC/14/14/0/0/5/100kHz//@DUTY_SYNC_EXT

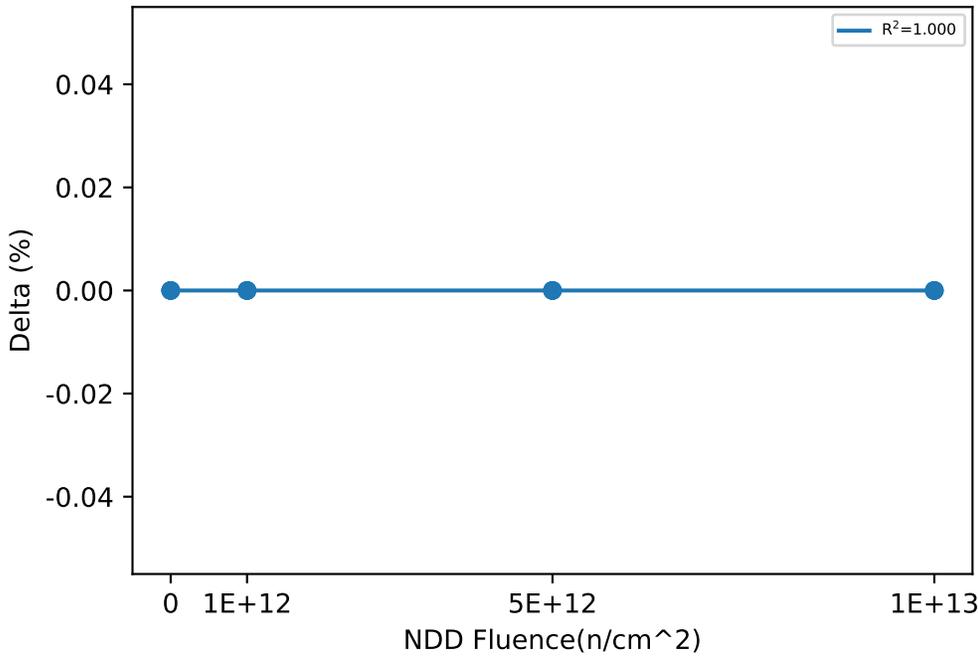## NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 40.0, Upper Limit = 60.0 (%))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	60	60	0
2	1e+12	NDD	60	60	0
3	1e+12	NDD	60	60	0
4	1e+12	NDD	60	60	0
5	5e+12	NDD	60	60	0
6	5e+12	NDD	60	60	0
7	5e+12	NDD	60	60	0
8	5e+12	NDD	60	60	0
9	1e+13	NDD	60	60	0
10	1e+13	NDD	60	60	0
11	1e+13	NDD	60	60	0
12	1e+13	NDD	60	60	0
91	0	CORRELATION	60	60	0
92	0	CORRELATION	60	60	0
93	0	CORRELATION	60	60	0
94	0	CORRELATION	60	60	0

Test Statistics (%)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	60	60	60	0	60	60	60	0	0	0	0	0
1e+12	60	60	60	0	60	60	60	0	0	0	0	0
5e+12	60	60	60	0	60	60	60	0	0	0	0	0
1e+13	60	60	60	0	60	60	60	0	0	0	0	0

Device Test: 20.35 LEVEL|FREQ/RT/12/12/0/0/5/200kHz//@FSW_EXT_RT_B

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 175.0, Upper Limit = 220.0 (kHz))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	192.89	193.02	0.128
2	1e+12	NDD	194.61	194.72	0.1062
3	1e+12	NDD	193.42	193.28	-0.1364
4	1e+12	NDD	192.78	192.88	0.094
5	5e+12	NDD	188.14	188.49	0.3539
6	5e+12	NDD	192.33	192.41	0.0838
7	5e+12	NDD	190.99	191.02	0.0314
8	5e+12	NDD	193.03	193.44	0.4062
9	1e+13	NDD	189.93	189.69	-0.2386
10	1e+13	NDD	195.05	194.31	-0.738
11	1e+13	NDD	195.45	194.96	-0.4939
12	1e+13	NDD	194.95	194.58	-0.3686
91	0	CORRELATION	193.74	193.81	0.0703
92	0	CORRELATION	195.33	195.37	0.0444
93	0	CORRELATION	193.18	193.13	-0.0432
94	0	CORRELATION	195.46	195.46	0
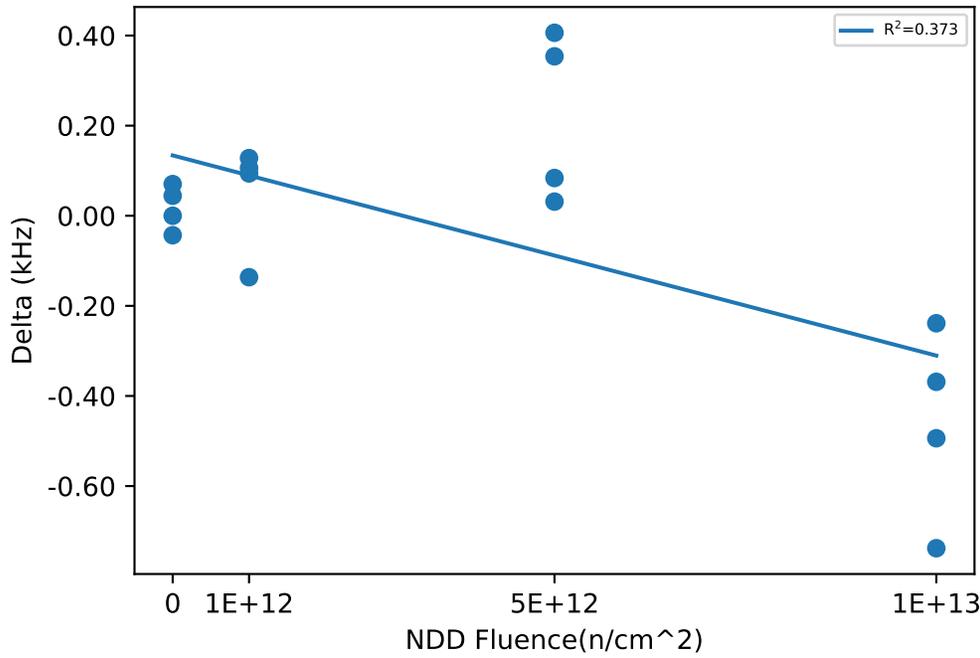
Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	193.18	194.43	195.46	1.1418	193.13	194.44	195.46	1.1561	-0.0432	0.017875	0.0703	0.050005
1e+12	192.78	193.43	194.61	0.83678	192.88	193.47	194.72	0.84503	-0.1364	0.04795	0.128	0.1237
5e+12	188.14	191.12	193.03	2.1612	188.49	191.34	193.44	2.1411	0.0314	0.21883	0.4062	0.1886
1e+13	189.93	193.85	195.45	2.6203	189.69	193.39	194.96	2.4781	-0.738	-0.45978	-0.2386	0.21276
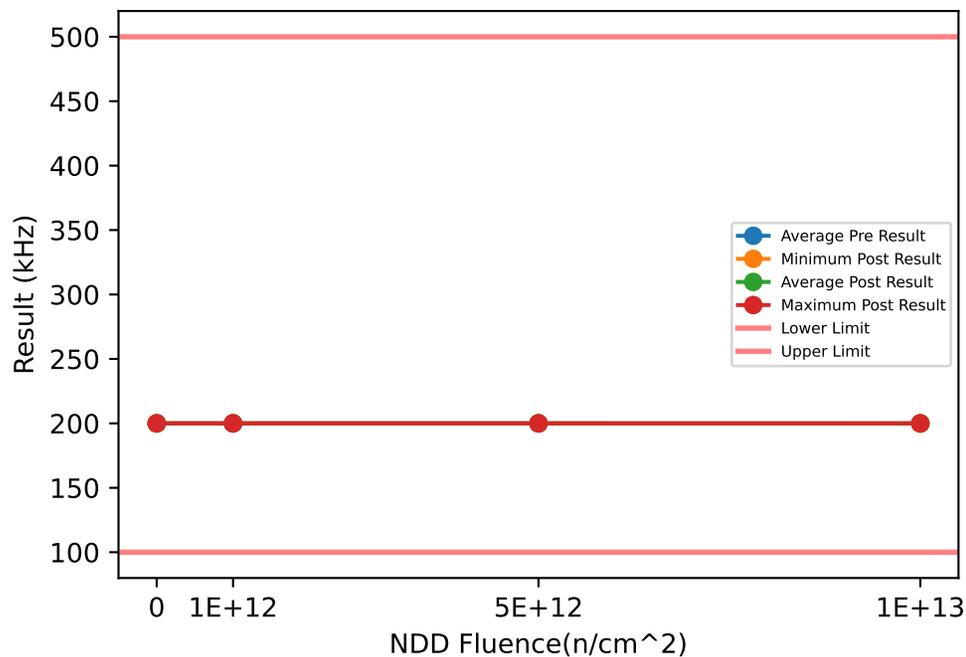
Device Test: 20.36 LEVEL|FREQ/SYNC/12/12/0/0/5/200kHz//@FREQ_SYNC_EXT_503X

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 100.0, Upper Limit = 500.0 (kHz))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	199.97	200	0.0325
2	1e+12	NDD	199.97	200.01	0.0353
3	1e+12	NDD	199.97	200	0.0252
4	1e+12	NDD	199.98	200	0.0166
5	5e+12	NDD	199.99	200	0.0041
6	5e+12	NDD	199.97	200	0.023
7	5e+12	NDD	199.97	200.01	0.0356
8	5e+12	NDD	199.98	200	0.0214
9	1e+13	NDD	200	200	0
10	1e+13	NDD	199.85	200.01	0.1593
11	1e+13	NDD	199.98	200	0.0284
12	1e+13	NDD	199.98	199.92	-0.0579
91	0	CORRELATION	199.98	200	0.0128
92	0	CORRELATION	199.97	200	0.0262
93	0	CORRELATION	199.97	200	0.0349
94	0	CORRELATION	199.98	200	0.0165
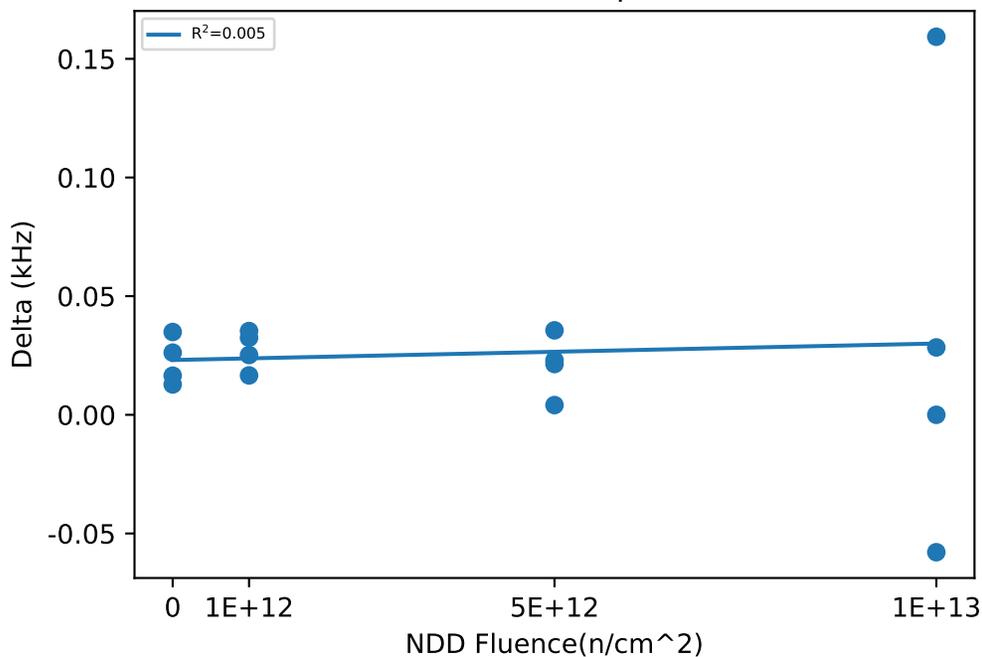
Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	199.97	199.98	199.98	0.0068542	200	200	200	0.0036313	0.0128	0.0226	0.0349	0.0099582
1e+12	199.97	199.97	199.98	0.0049243	200	200	200.01	0.0041508	0.0166	0.0274	0.0353	0.0083646
5e+12	199.97	199.98	199.99	0.0096026	200	200	200.01	0.0044684	0.0041	0.021025	0.0356	0.012948
1e+13	199.85	199.95	200	0.070362	199.92	199.98	200.01	0.039112	-0.0579	0.03245	0.1593	0.091876
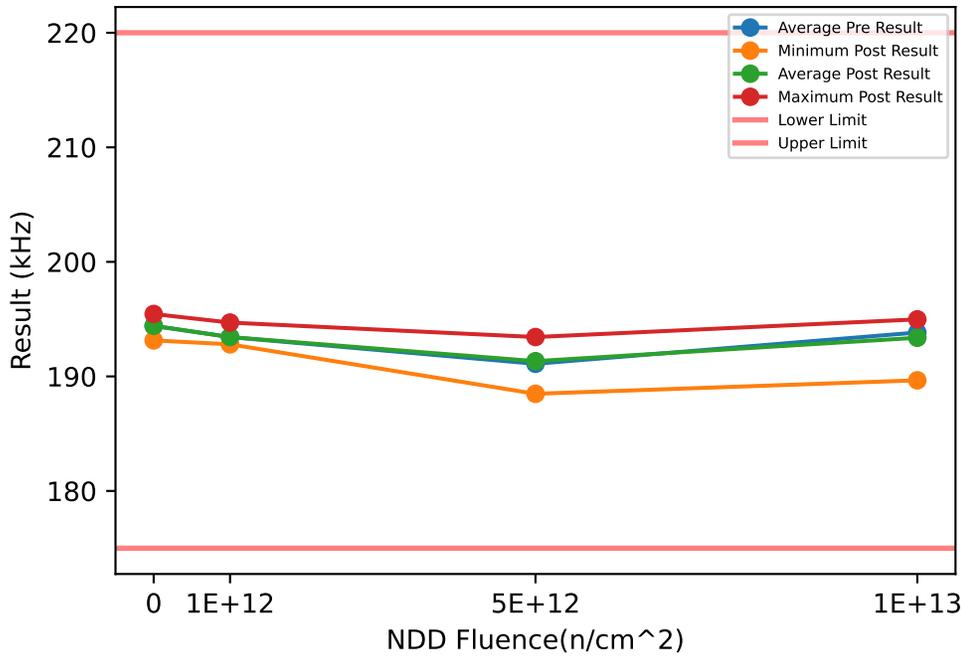
Device Test: 20.37 LEVEL|FREQ/RT/14/14/0/0/5/200kHz//@FSW_EXT_RT_B

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 175.0, Upper Limit = 220.0 (kHz))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	192.9	193	0.1057
2	1e+12	NDD	194.64	194.7	0.0599
3	1e+12	NDD	193.4	193.24	-0.1627
4	1e+12	NDD	192.79	192.8	0.0071
5	5e+12	NDD	188.11	188.48	0.3719
6	5e+12	NDD	192.3	192.42	0.1114
7	5e+12	NDD	190.98	190.99	0.015
8	5e+12	NDD	193.01	193.44	0.423
9	1e+13	NDD	189.91	189.66	-0.2557
10	1e+13	NDD	195.05	194.31	-0.7395
11	1e+13	NDD	195.42	194.98	-0.4444
12	1e+13	NDD	194.94	194.55	-0.3891
91	0	CORRELATION	193.72	193.75	0.0298
92	0	CORRELATION	195.31	195.34	0.0248
93	0	CORRELATION	193.16	193.15	-0.0129
94	0	CORRELATION	195.45	195.45	-0.0043
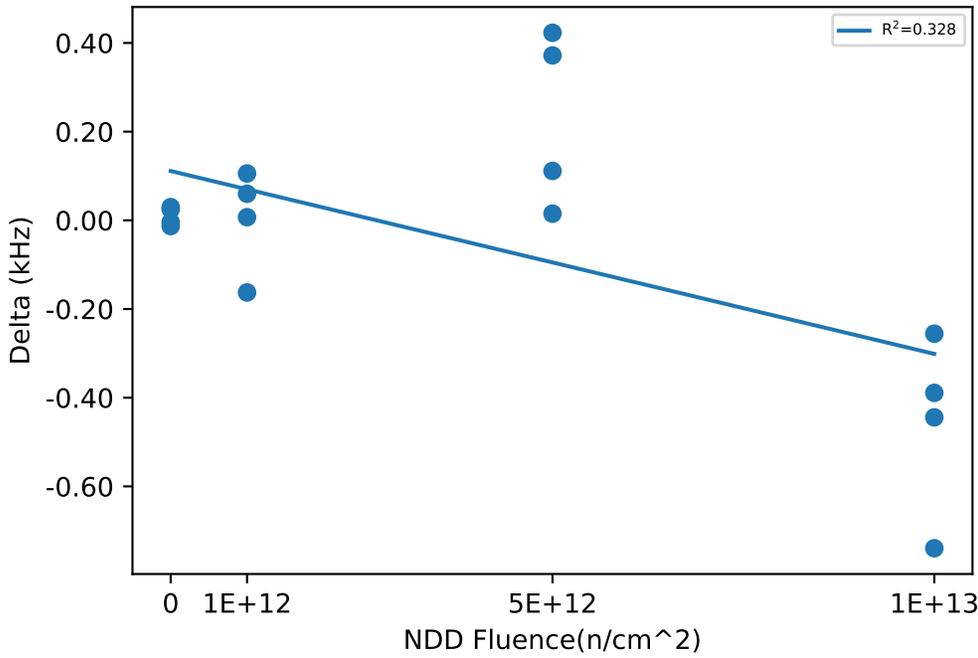
Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	193.16	194.41	195.45	1.1469	193.15	194.42	195.45	1.151	-0.0129	0.00935	0.0298	0.021121
1e+12	192.79	193.43	194.64	0.84661	192.8	193.44	194.7	0.86085	-0.1627	0.0025	0.1057	0.11727
5e+12	188.11	191.1	193.01	2.1654	188.48	191.33	193.44	2.148	0.015	0.23032	0.423	0.19805
1e+13	189.91	193.83	195.42	2.6202	189.66	193.38	194.98	2.4931	-0.7395	-0.45717	-0.2557	0.2042
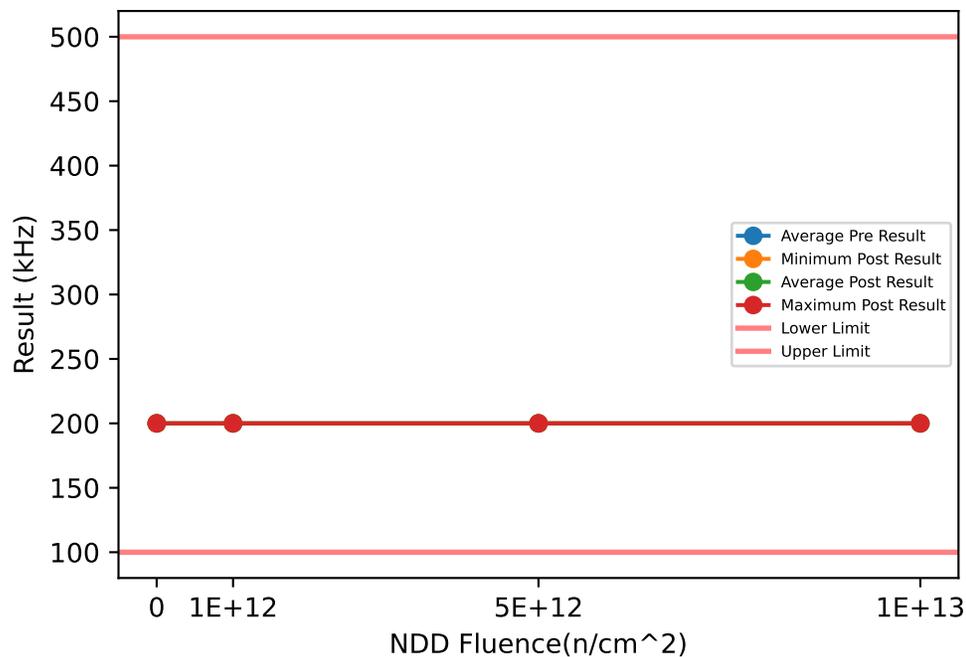
Device Test: 20.38 LEVEL|FREQ/SYNC/14/14/0/0/5/200kHz//@FREQ_SYNC_EXT_503X

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 100.0, Upper Limit = 500.0 (kHz))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	199.98	200	0.0227
2	1e+12	NDD	199.97	200	0.0323
3	1e+12	NDD	199.97	200	0.028
4	1e+12	NDD	199.98	200	0.0201
5	5e+12	NDD	200	199.99	-0.0011
6	5e+12	NDD	199.98	200	0.0153
7	5e+12	NDD	199.97	200	0.0381
8	5e+12	NDD	199.98	200	0.0198
9	1e+13	NDD	199.97	200	0.0313
10	1e+13	NDD	199.97	200	0.026
11	1e+13	NDD	199.97	200	0.0291
12	1e+13	NDD	199.98	200	0.0207
91	0	CORRELATION	199.99	199.99	0.0022
92	0	CORRELATION	199.97	199.99	0.0198
93	0	CORRELATION	199.98	200	0.0277
94	0	CORRELATION	199.98	200	0.0225
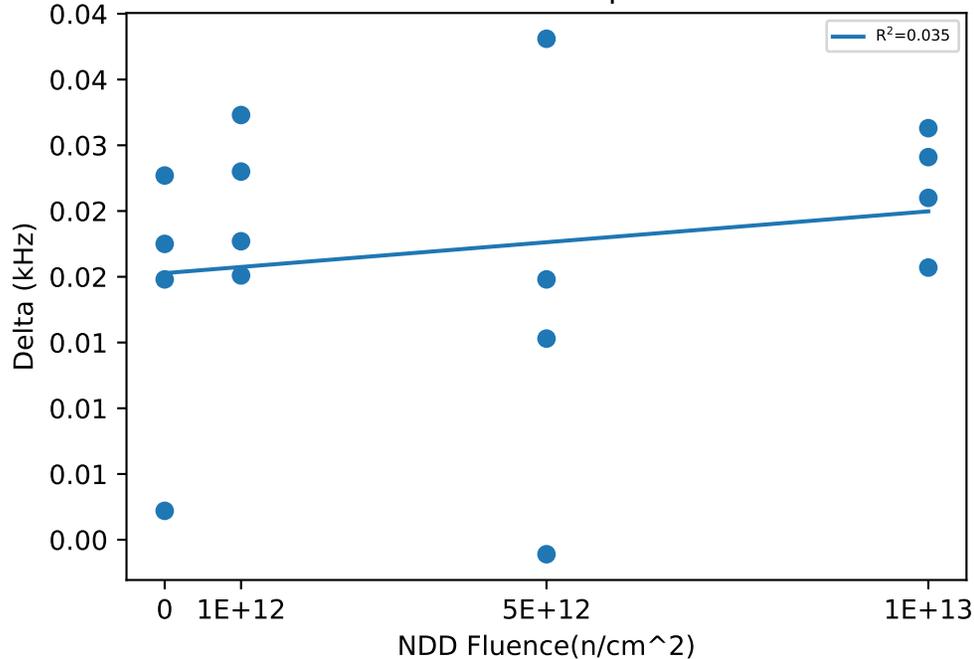
Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	199.97	199.98	199.99	0.0078388	199.99	200	200	0.0045996	0.0022	0.01805	0.0277	0.011064
1e+12	199.97	199.98	199.98	0.0046047	200	200	200	0.0011177	0.0201	0.025775	0.0323	0.0054524
5e+12	199.97	199.98	200	0.011566	199.99	200	200	0.0050445	-0.0011	0.018025	0.0381	0.016118
1e+13	199.97	199.97	199.98	0.0058492	200	200	200	0.0025838	0.0207	0.026775	0.0313	0.0045966
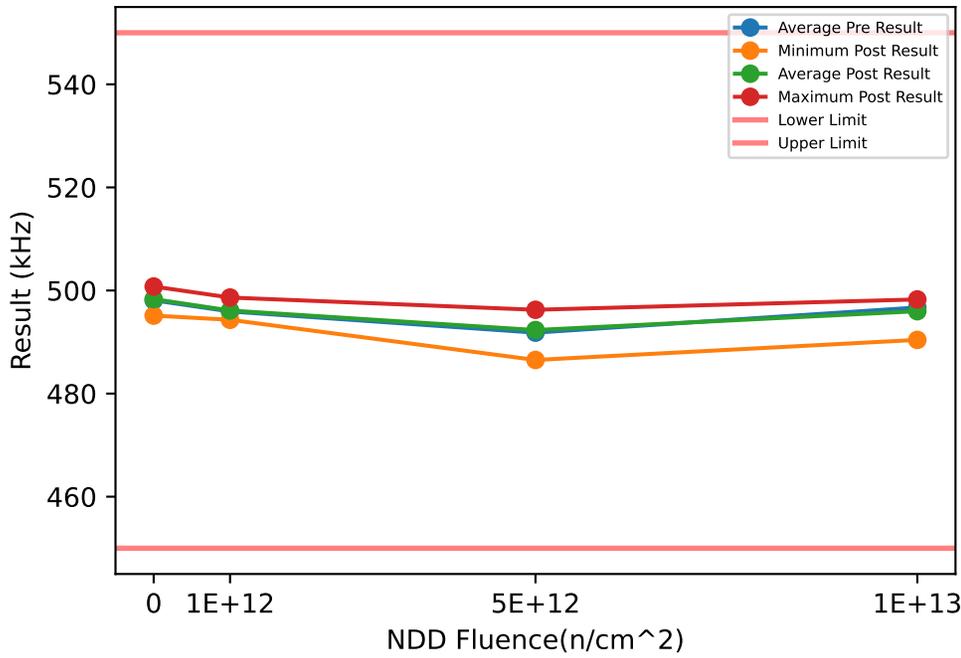
# Device Test: 20.39 LEVEL|FREQ/RT/12/12/0/0/5/500kHz//@FSW_EXT_RT_C

NDD vs Result Stats

Test Results (Lower Limit = 450.0, Upper Limit = 550.0 (kHz))

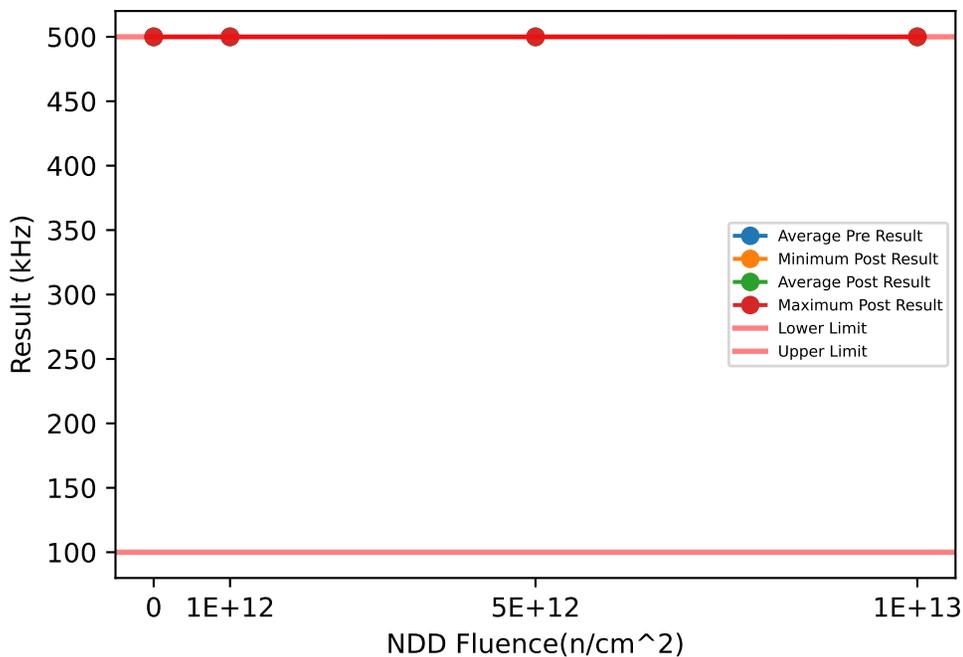| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	496.29	496.67	0.3722
2	1e+12	NDD	498.35	498.63	0.2819
3	1e+12	NDD	494.94	494.85	-0.0892
4	1e+12	NDD	494.15	494.32	0.1658
5	5e+12	NDD	485.94	486.52	0.58
6	5e+12	NDD	493.8	494.11	0.3114
7	5e+12	NDD	492.13	492.42	0.2951
8	5e+12	NDD	495.43	496.26	0.8287
9	1e+13	NDD	491.11	490.42	-0.6872
10	1e+13	NDD	498.28	497.3	-0.9833
11	1e+13	NDD	498.55	497.95	-0.5997
12	1e+13	NDD	498.87	498.26	-0.6085
91	0	CORRELATION	494.86	495.13	0.2696
92	0	CORRELATION	499.81	500.09	0.2769
93	0	CORRELATION	497.15	497.33	0.1856
94	0	CORRELATION	500.55	500.77	0.2202

NDD vs Post - Pre Exposure Delta
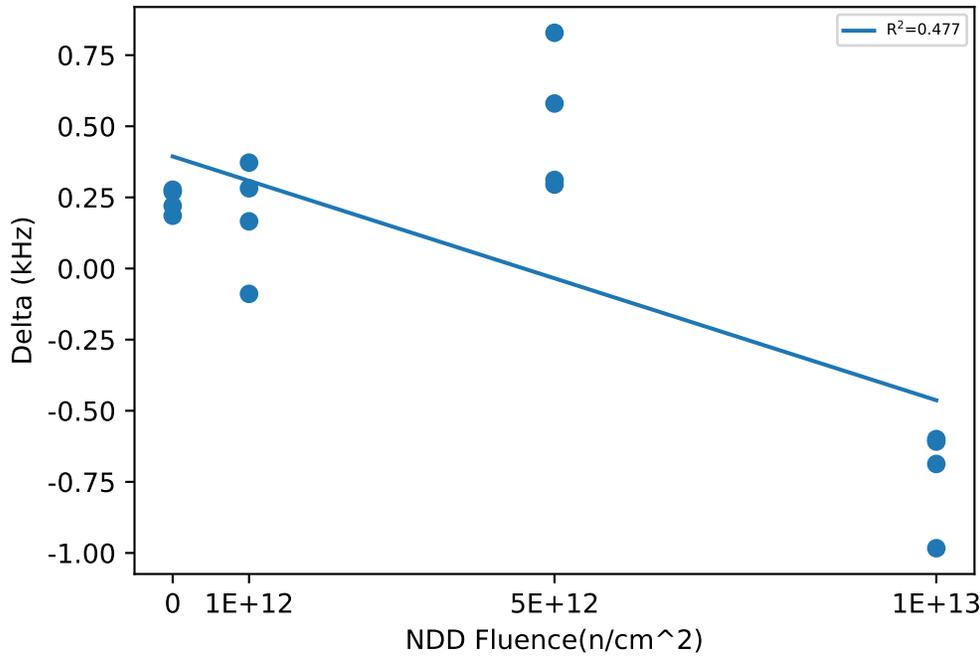
Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	494.86	498.09	500.55	2.6042	495.13	498.33	500.77	2.6007	0.1856	0.23808	0.2769	0.043106
1e+12	494.15	495.93	498.35	1.8386	494.32	496.11	498.63	1.9562	-0.0892	0.18268	0.3722	0.19997
5e+12	485.94	491.82	495.43	4.1467	486.52	492.33	496.26	4.1768	0.2951	0.5038	0.8287	0.25294
1e+13	491.11	496.7	498.87	3.7387	490.42	495.98	498.26	3.7309	-0.9833	-0.71968	-0.5997	0.1801

Device Test: 20.40 LEVEL|FREQ/SYNC/12/12/0/0/5/500kHz//@FREQ_SYNC_EXT_503X

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 100.0, Upper Limit = 500.0 (kHz))

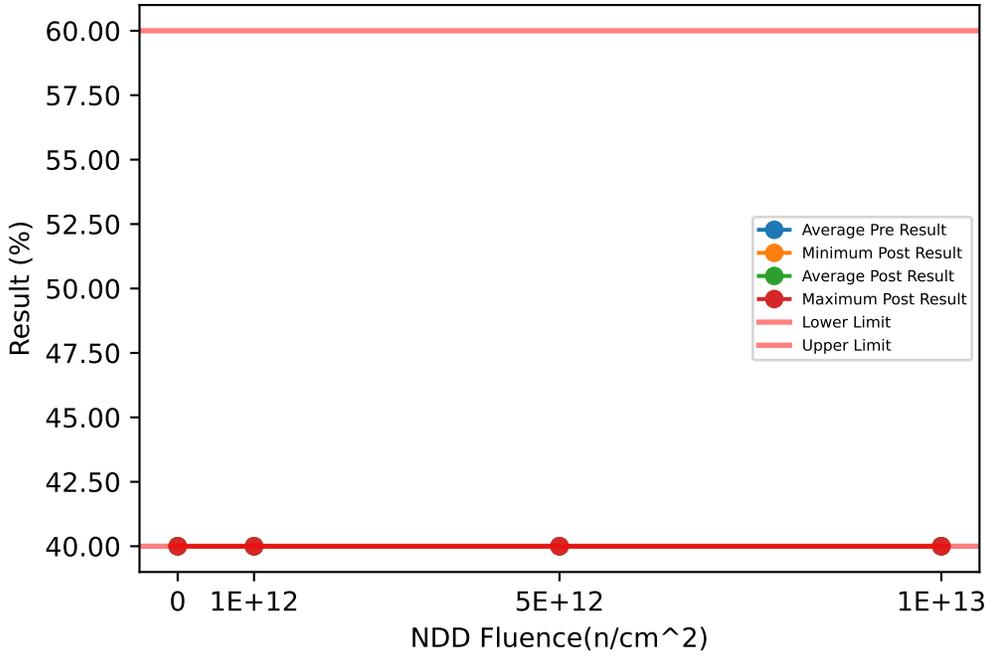| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	500.01	499.99	-0.0128
2	1e+12	NDD	499.83	500.02	0.1954
3	1e+12	NDD	499.85	500.02	0.1702
4	1e+12	NDD	499.88	499.99	0.1157
5	5e+12	NDD	499.96	500.01	0.0504
6	5e+12	NDD	499.85	500.02	0.1721
7	5e+12	NDD	499.85	499.98	0.1305
8	5e+12	NDD	499.85	499.98	0.1317
9	1e+13	NDD	499.86	500.03	0.1747
10	1e+13	NDD	499.82	500	0.1839
11	1e+13	NDD	499.79	500.01	0.2176
12	1e+13	NDD	499.84	500.03	0.1858
91	0	CORRELATION	499.88	500.01	0.1264
92	0	CORRELATION	499.81	499.99	0.1712
93	0	CORRELATION	499.83	500.02	0.1901
94	0	CORRELATION	499.88	500.02	0.1356
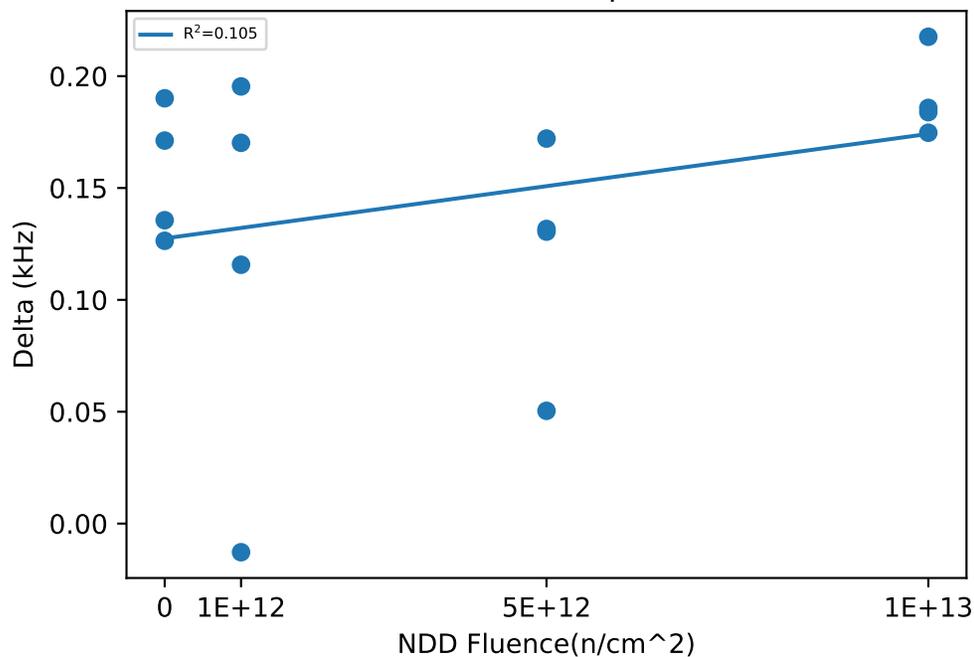
Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	499.81	499.85	499.88	0.033841	499.99	500.01	500.02	0.015788	0.1264	0.15582	0.1901	0.029922
1e+12	499.83	499.89	500.01	0.080202	499.99	500.01	500.02	0.016803	-0.0128	0.11712	0.1954	0.092784
5e+12	499.85	499.88	499.96	0.057121	499.98	500	500.02	0.023711	0.0504	0.12117	0.1721	0.050991
1e+13	499.79	499.83	499.86	0.027256	500	500.02	500.03	0.014303	0.1747	0.1905	0.2176	0.018706

Device Test: 20.41 PF|DCL_40/SYNC/12/12/0/0/5/500kHz//@DUTY_SYNC_EXT

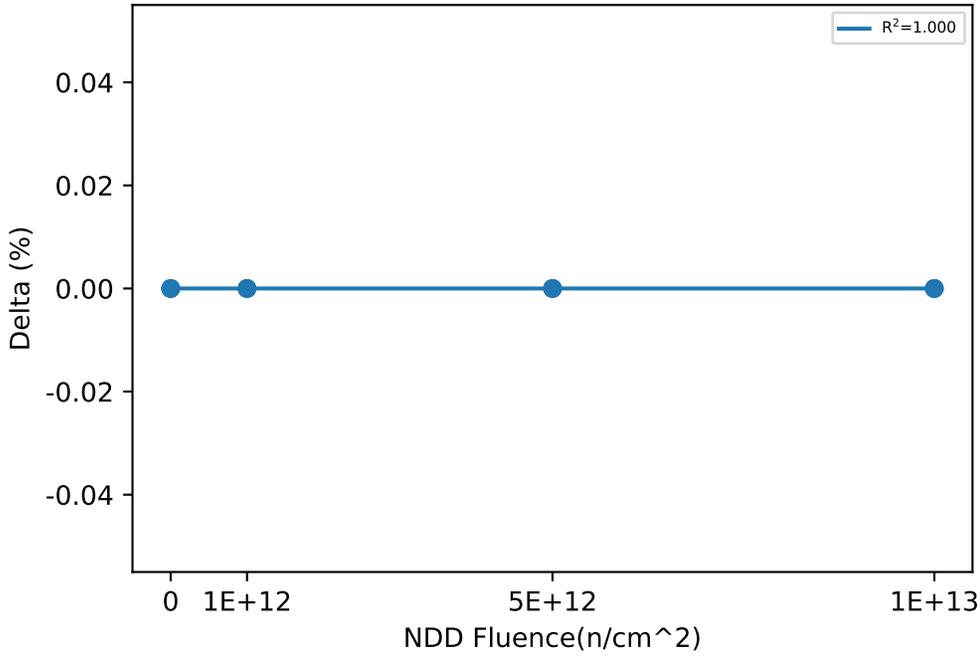## NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 40.0, Upper Limit = 60.0 (%))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	40	40	0
2	1e+12	NDD	40	40	0
3	1e+12	NDD	40	40	0
4	1e+12	NDD	40	40	0
5	5e+12	NDD	40	40	0
6	5e+12	NDD	40	40	0
7	5e+12	NDD	40	40	0
8	5e+12	NDD	40	40	0
9	1e+13	NDD	40	40	0
10	1e+13	NDD	40	40	0
11	1e+13	NDD	40	40	0
12	1e+13	NDD	40	40	0
91	0	CORRELATION	40	40	0
92	0	CORRELATION	40	40	0
93	0	CORRELATION	40	40	0
94	0	CORRELATION	40	40	0

Test Statistics (%)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	40	40	40	0	40	40	40	0	0	0	0	0
1e+12	40	40	40	0	40	40	40	0	0	0	0	0
5e+12	40	40	40	0	40	40	40	0	0	0	0	0
1e+13	40	40	40	0	40	40	40	0	0	0	0	0

Device Test: 20.42 PF|DCL_60/SYNC/12/12/0/0/5/500kHz//@DUTY_SYNC_EXT

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 40.0, Upper Limit = 60.0 (%))

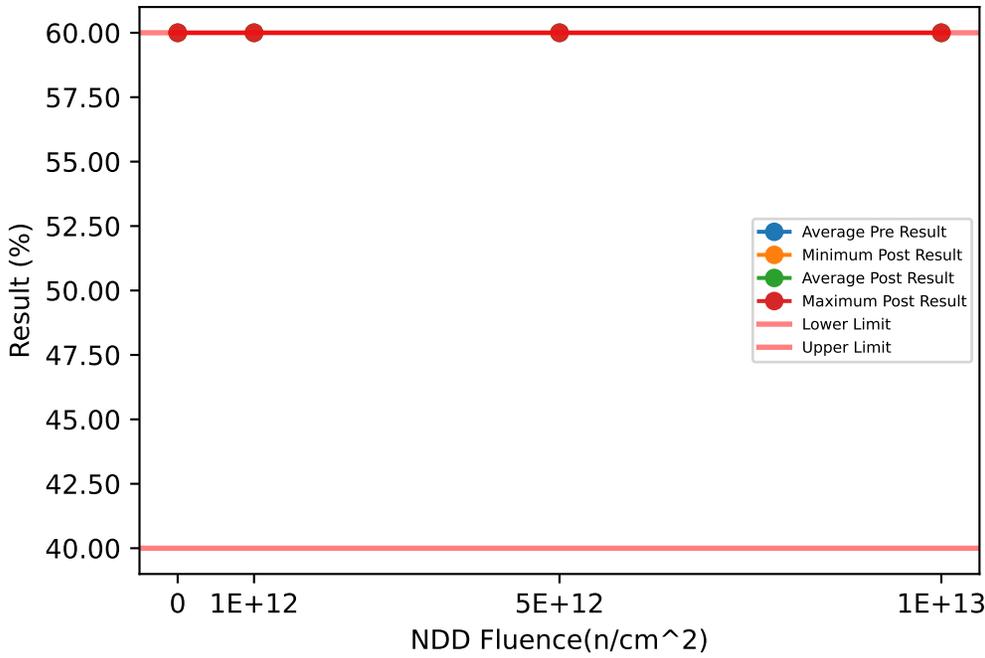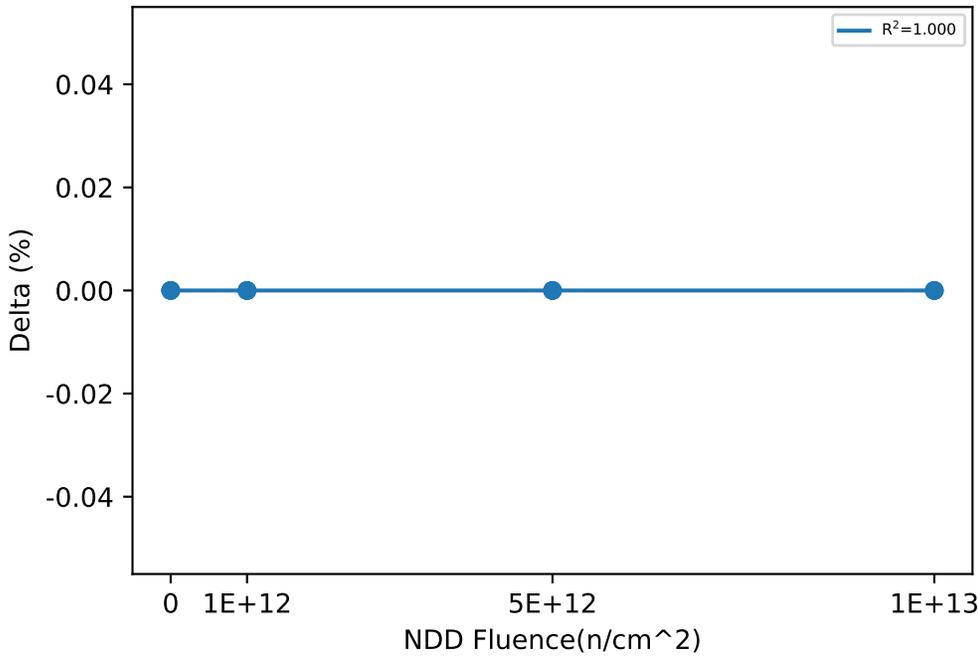| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	60	60	0
2	1e+12	NDD	60	60	0
3	1e+12	NDD	60	60	0
4	1e+12	NDD	60	60	0
5	5e+12	NDD	60	60	0
6	5e+12	NDD	60	60	0
7	5e+12	NDD	60	60	0
8	5e+12	NDD	60	60	0
9	1e+13	NDD	60	60	0
10	1e+13	NDD	60	60	0
11	1e+13	NDD	60	60	0
12	1e+13	NDD	60	60	0
91	0	CORRELATION	60	60	0
92	0	CORRELATION	60	60	0
93	0	CORRELATION	60	60	0
94	0	CORRELATION	60	60	0

Test Statistics (%)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	60	60	60	0	60	60	60	0	0	0	0	0
1e+12	60	60	60	0	60	60	60	0	0	0	0	0
5e+12	60	60	60	0	60	60	60	0	0	0	0	0
1e+13	60	60	60	0	60	60	60	0	0	0	0	0

Device Test: 20.43 LEVEL|FREQ/RT/14/14/0/0/5/500kHz//@FSW_EXT_RT_C

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 450.0, Upper Limit = 550.0 (kHz))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	496.24	496.57	0.3397
2	1e+12	NDD	498.26	498.61	0.3447
3	1e+12	NDD	494.96	494.8	-0.1629
4	1e+12	NDD	494.03	494.3	0.27
5	5e+12	NDD	485.89	486.49	0.5999
6	5e+12	NDD	493.76	493.99	0.2303
7	5e+12	NDD	492.07	492.37	0.3006
8	5e+12	NDD	495.44	496.24	0.804
9	1e+13	NDD	491.03	490.42	-0.614
10	1e+13	NDD	498.32	497.25	-1.0645
11	1e+13	NDD	498.52	497.87	-0.6436
12	1e+13	NDD	498.76	498.26	-0.5053
91	0	CORRELATION	494.87	495.12	0.2557
92	0	CORRELATION	499.81	500.09	0.2785
93	0	CORRELATION	497.13	497.23	0.1018
94	0	CORRELATION	500.6	500.73	0.1327
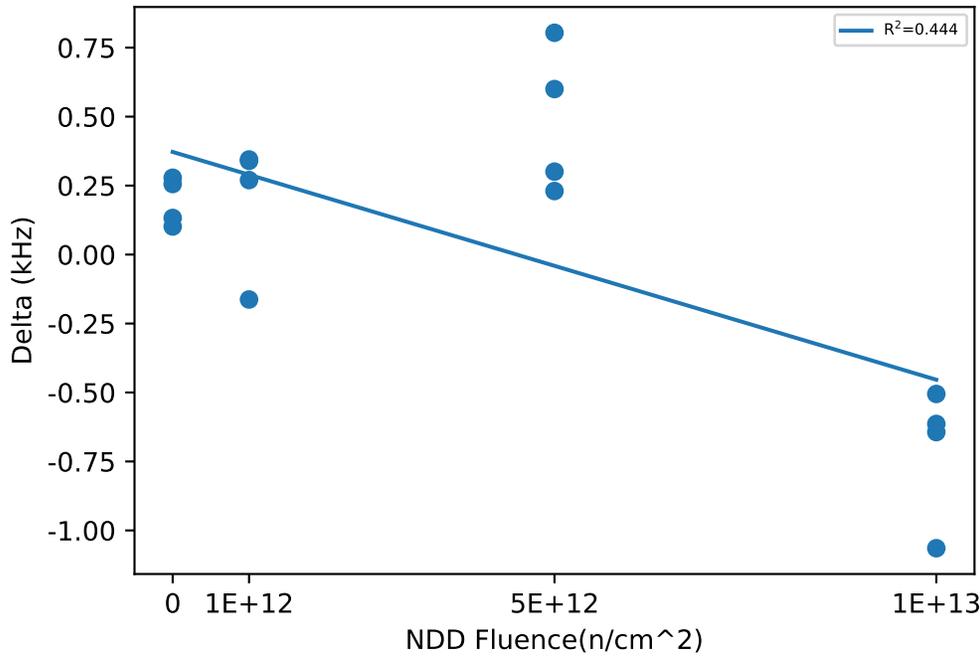
Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	494.87	498.1	500.6	2.6191	495.12	498.29	500.73	2.6055	0.1018	0.19218	0.2785	0.087925
1e+12	494.03	495.87	498.26	1.8298	494.3	496.07	498.61	1.9509	-0.1629	0.19787	0.3447	0.24292
5e+12	485.89	491.79	495.44	4.1672	486.49	492.27	496.24	4.1703	0.2303	0.4837	0.804	0.26698
1e+13	491.03	496.66	498.76	3.7563	490.42	495.95	498.26	3.7131	-1.0645	-0.70685	-0.5053	0.24574
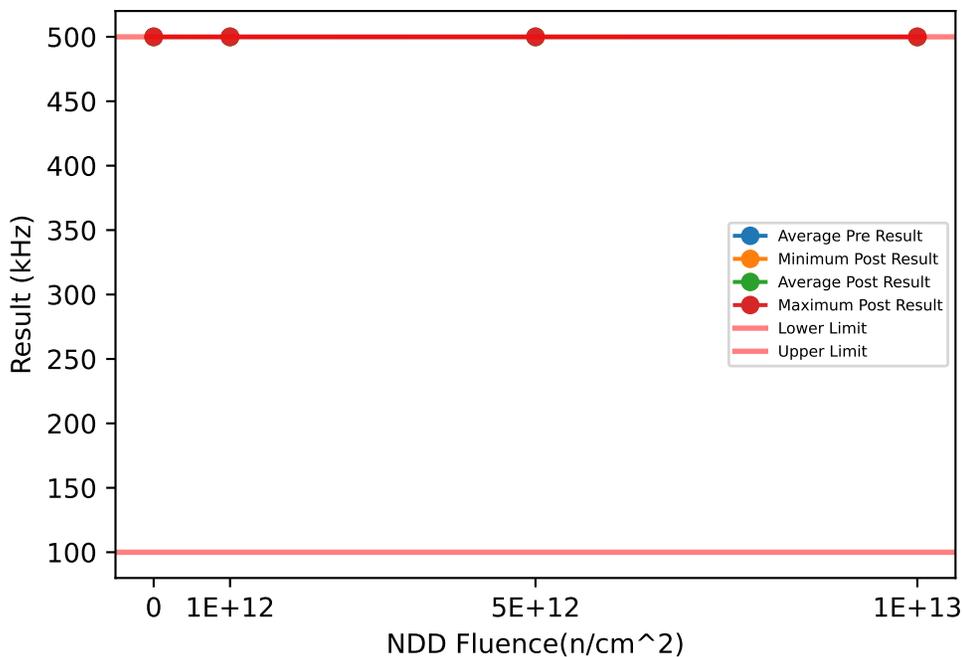
Device Test: 20.44 LEVEL|FREQ/SYNC/14/14/0/0/5/500kHz//@FREQ_SYNC_EXT_503X

NDD vs Result Stats

Legend:
- Average Pre Result
- Minimum Post Result
- Average Post Result
- Maximum Post Result
- Lower Limit
- Upper Limit

NDD vs Post - Pre Exposure Delta

$R^2=0.029$

Test Results (Lower Limit = 100.0, Upper Limit = 500.0 (kHz))

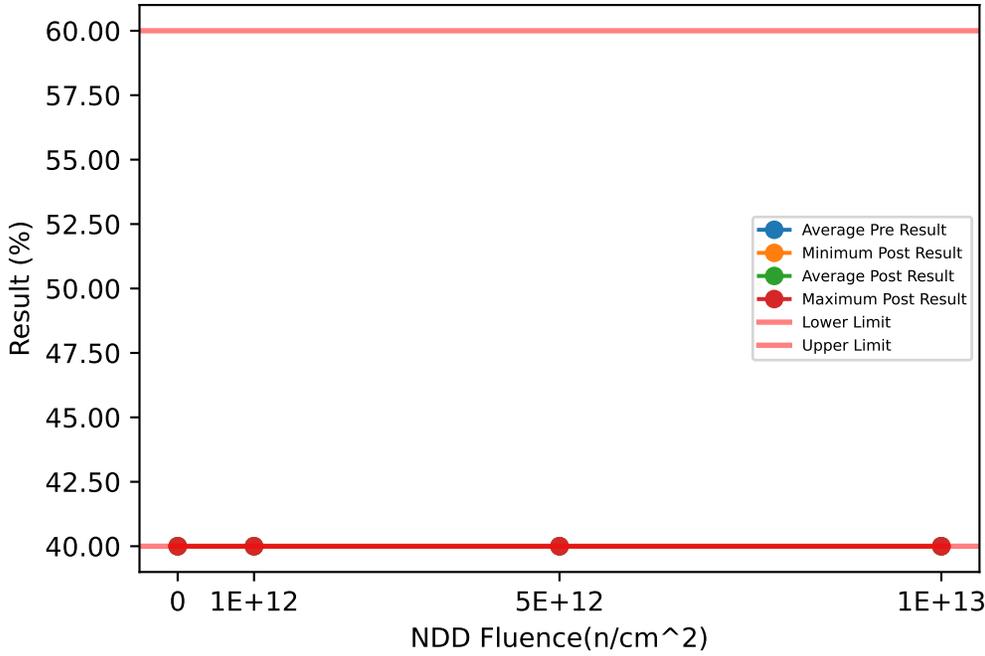| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	499.97	500.02	0.0493
2	1e+12	NDD	499.83	499.99	0.1647
3	1e+12	NDD	499.84	500.02	0.1759
4	1e+12	NDD	499.88	500.02	0.1343
5	5e+12	NDD	499.95	500	0.0407
6	5e+12	NDD	499.86	500.04	0.1814
7	5e+12	NDD	499.81	499.99	0.1787
8	5e+12	NDD	499.88	500.03	0.1467
9	1e+13	NDD	499.95	499.97	0.0223
10	1e+13	NDD	499.84	499.99	0.1467
11	1e+13	NDD	499.79	500.02	0.2242
12	1e+13	NDD	499.84	500.02	0.1724
91	0	CORRELATION	500.01	499.96	-0.0502
92	0	CORRELATION	499.86	500.03	0.1693
93	0	CORRELATION	499.83	500.01	0.1838
94	0	CORRELATION	499.88	499.98	0.0971
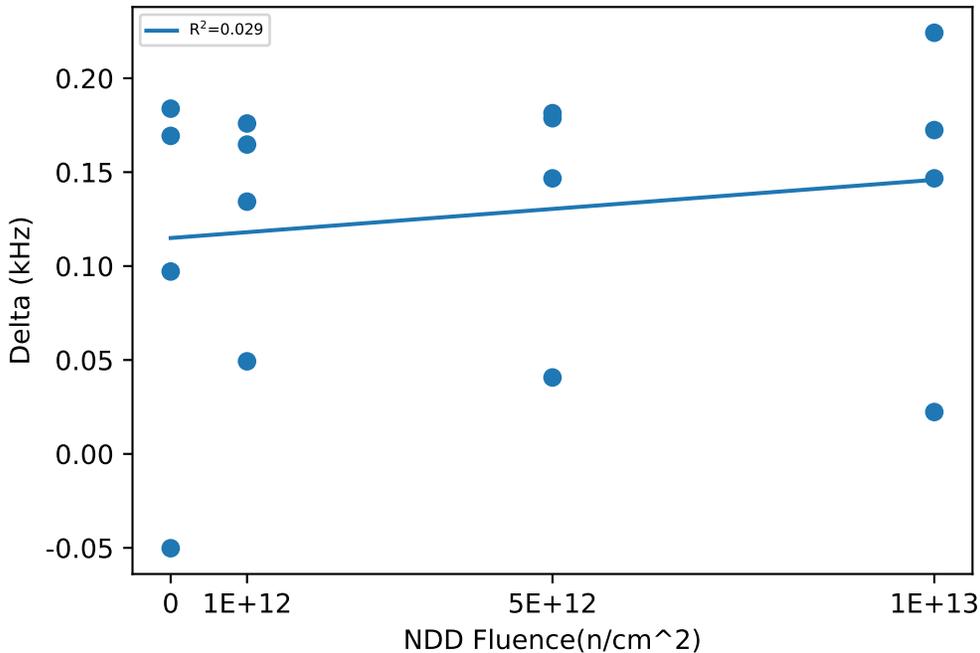
Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	499.83	499.9	500.01	0.081739	499.96	500	500.03	0.030821	-0.0502	0.1	0.1838	0.10707
1e+12	499.83	499.88	499.97	0.061903	499.99	500.01	500.02	0.012265	0.0493	0.13105	0.1759	0.057264
5e+12	499.81	499.87	499.95	0.061162	499.99	500.01	500.04	0.026109	0.0407	0.13688	0.1814	0.066025
1e+13	499.79	499.86	499.95	0.066751	499.97	500	500.02	0.021027	0.0223	0.1414	0.2242	0.085693

Device Test: 20.45 PF|DCL_40/SYNC/14/14/0/0/5/500kHz//@DUTY_SYNC_EXT

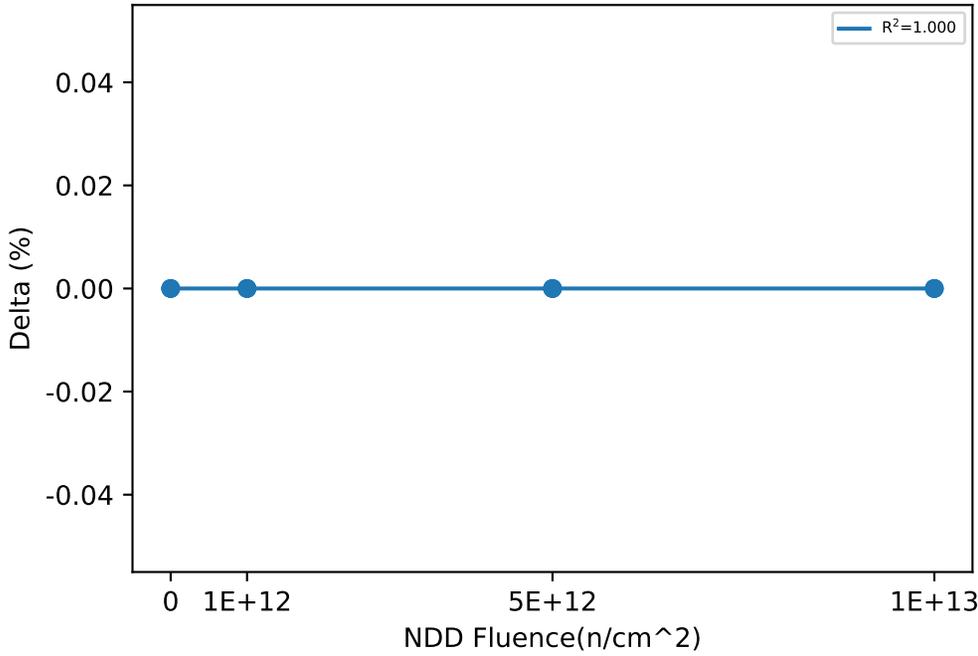## NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 40.0, Upper Limit = 60.0 (%))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	40	40	0
2	1e+12	NDD	40	40	0
3	1e+12	NDD	40	40	0
4	1e+12	NDD	40	40	0
5	5e+12	NDD	40	40	0
6	5e+12	NDD	40	40	0
7	5e+12	NDD	40	40	0
8	5e+12	NDD	40	40	0
9	1e+13	NDD	40	40	0
10	1e+13	NDD	40	40	0
11	1e+13	NDD	40	40	0
12	1e+13	NDD	40	40	0
91	0	CORRELATION	40	40	0
92	0	CORRELATION	40	40	0
93	0	CORRELATION	40	40	0
94	0	CORRELATION	40	40	0

Test Statistics (%)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	40	40	40	0	40	40	40	0	0	0	0	0
1e+12	40	40	40	0	40	40	40	0	0	0	0	0
5e+12	40	40	40	0	40	40	40	0	0	0	0	0
1e+13	40	40	40	0	40	40	40	0	0	0	0	0

Device Test: 20.46 PF|DCL_60/SYNC/14/14/0/0/5/500kHz//@DUTY_SYNC_EXT

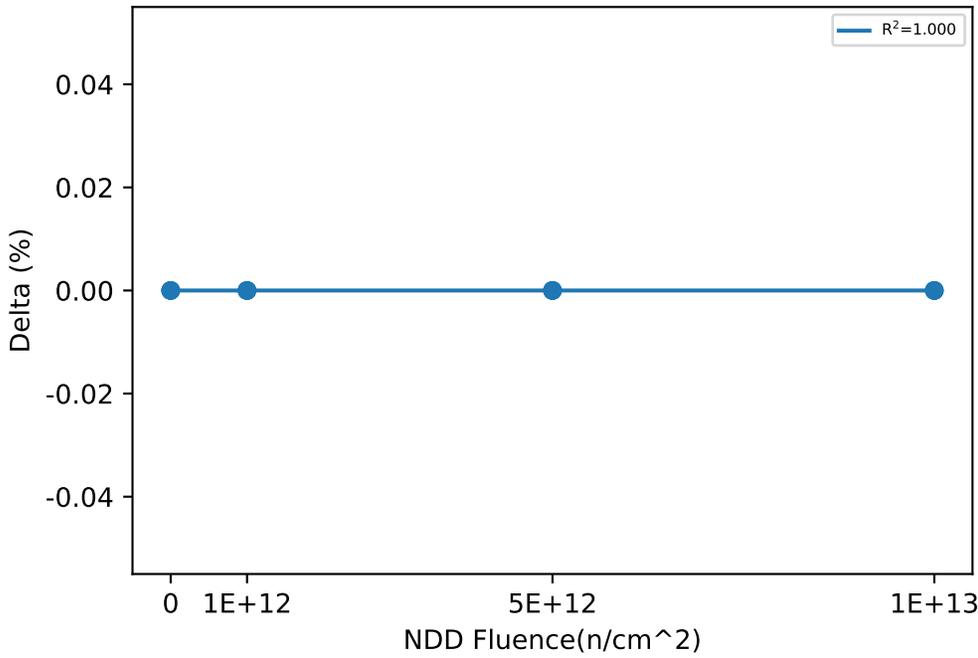## NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 40.0, Upper Limit = 60.0 (%))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	60	60	0
2	1e+12	NDD	60	60	0
3	1e+12	NDD	60	60	0
4	1e+12	NDD	60	60	0
5	5e+12	NDD	60	60	0
6	5e+12	NDD	60	60	0
7	5e+12	NDD	60	60	0
8	5e+12	NDD	60	60	0
9	1e+13	NDD	60	60	0
10	1e+13	NDD	60	60	0
11	1e+13	NDD	60	60	0
12	1e+13	NDD	60	60	0
91	0	CORRELATION	60	60	0
92	0	CORRELATION	60	60	0
93	0	CORRELATION	60	60	0
94	0	CORRELATION	60	60	0

Test Statistics (%)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	60	60	60	0	60	60	60	0	0	0	0	0
1e+12	60	60	60	0	60	60	60	0	0	0	0	0
5e+12	60	60	60	0	60	60	60	0	0	0	0	0
1e+13	60	60	60	0	60	60	60	0	0	0	0	0

Device Test: 20.47 LEVEL|FREQ/RT/12/12/0/1000/5/100kHz//@FSW_EXT_RT_A

NDD vs Result Stats

Test Results (Lower Limit = 80.0, Upper Limit = 110.0 (kHz))

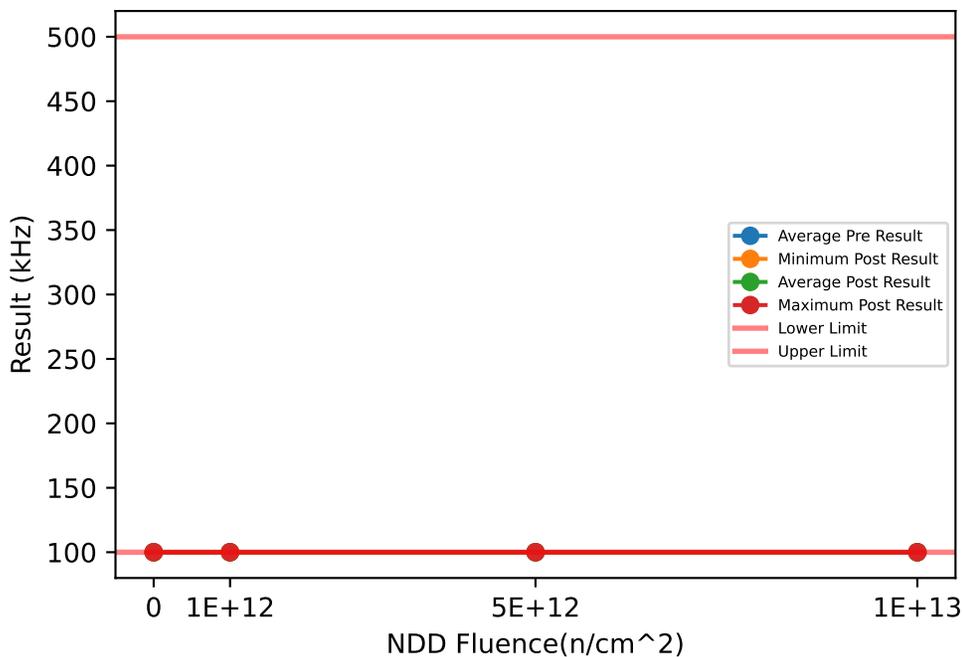| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	92.908	92.958	0.0505
2	1e+12	NDD	94.073	94.107	0.0338
3	1e+12	NDD	93.723	93.605	-0.1186
4	1e+12	NDD	93.209	93.218	0.0088
5	5e+12	NDD	90.329	90.57	0.2405
6	5e+12	NDD	92.69	92.752	0.0624
7	5e+12	NDD	91.801	91.74	-0.0608
8	5e+12	NDD	93.013	93.305	0.2927
9	1e+13	NDD	91.041	90.945	-0.0954
10	1e+13	NDD	94.511	94.01	-0.5006
11	1e+13	NDD	94.882	94.573	-0.3097
12	1e+13	NDD	94.197	93.93	-0.2667
91	0	CORRELATION	93.947	93.976	0.0291
92	0	CORRELATION	94.493	94.519	0.0251
93	0	CORRELATION	92.985	92.957	-0.0289
94	0	CORRELATION	94.57	94.58	0.0101

NDD vs Post - Pre Exposure Delta
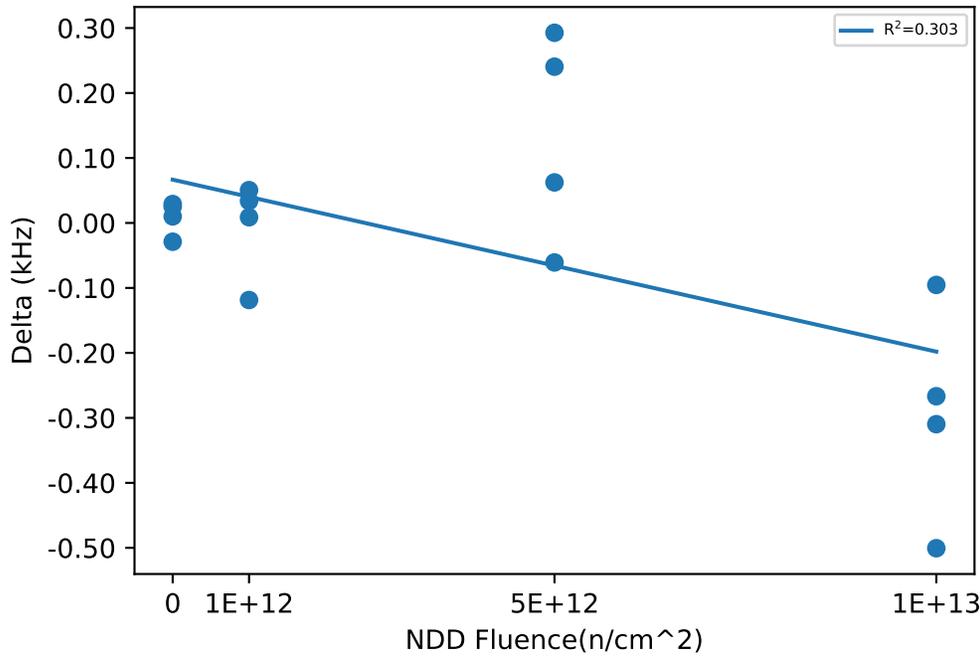
Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	92.985	93.999	94.57	0.73048	92.957	94.008	94.58	0.75162	-0.0289	0.00885	0.0291	0.026462
1e+12	92.908	93.478	94.073	0.52022	92.958	93.472	94.107	0.49978	-0.1186	-0.006375	0.0505	0.076754
5e+12	90.329	91.958	93.013	1.2008	90.57	92.092	93.305	1.204	-0.0608	0.1337	0.2927	0.16289
1e+13	91.041	93.658	94.882	1.767	90.945	93.365	94.573	1.6379	-0.5006	-0.2931	-0.0954	0.16645

Device Test: 20.48 LEVEL|FREQ/SYNC/12/12/0/1000/5/100kHz//@FREQ_SYNC_EXT_503X

## NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 100.0, Upper Limit = 500.0 (kHz))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	99.999	99.999	-0.0004
2	1e+12	NDD	99.995	100	0.006
3	1e+12	NDD	99.994	100	0.0071
4	1e+12	NDD	99.996	100	0.0058
5	5e+12	NDD	99.997	100	0.0036
6	5e+12	NDD	99.994	100	0.0066
7	5e+12	NDD	99.992	100	0.0083
8	5e+12	NDD	99.994	99.999	0.0045
9	1e+13	NDD	99.998	100	0.0015
10	1e+13	NDD	99.995	99.999	0.0044
11	1e+13	NDD	99.992	100	0.0086
12	1e+13	NDD	99.996	100	0.0044
91	0	CORRELATION	99.999	100	0.0014
92	0	CORRELATION	99.993	100	0.0076
93	0	CORRELATION	99.994	100	0.007
94	0	CORRELATION	99.994	100	0.0079
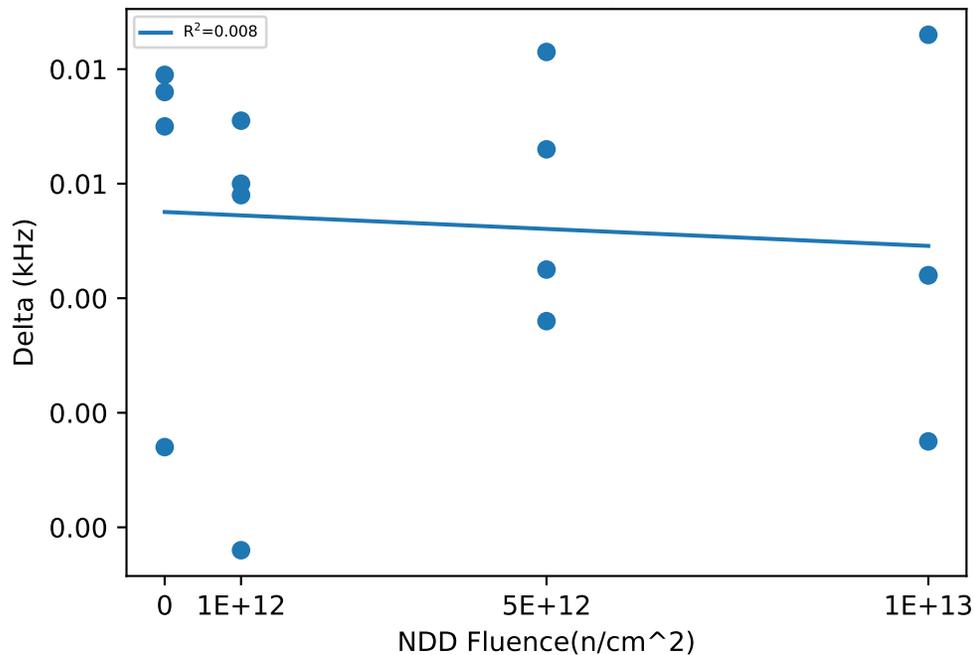
Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	99.993	99.995	99.999	0.0026357	100	100	100	0.00063966	0.0014	0.005975	0.0079	0.0030729
1e+12	99.994	99.996	99.999	0.0022166	99.999	100	100	0.0012176	-0.0004	0.004625	0.0071	0.0033984
5e+12	99.992	99.994	99.997	0.001841	99.999	100	100	0.00099457	0.0036	0.00575	0.0083	0.0021142
1e+13	99.992	99.995	99.998	0.0025552	99.999	100	100	0.00049666	0.0015	0.004725	0.0086	0.0029228
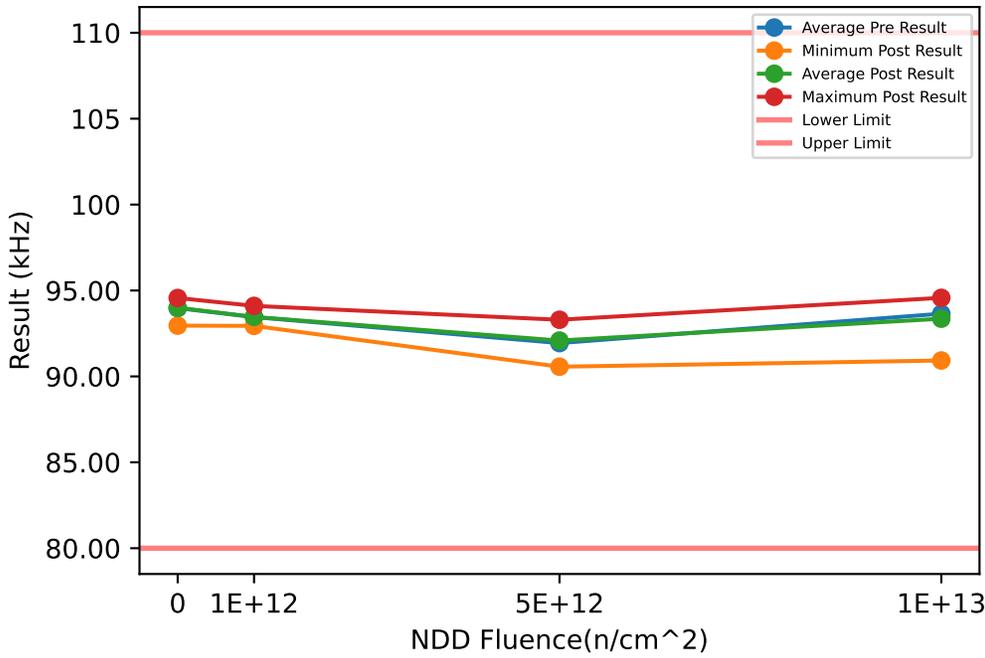
Device Test: 20.49 LEVEL|FREQ/RT/14/14/0/1000/5/100kHz//@FSW_EXT_RT_A

## NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 80.0, Upper Limit = 110.0 (kHz))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	92.875	92.942	0.0668
2	1e+12	NDD	94.056	94.104	0.0474
3	1e+12	NDD	93.687	93.594	-0.0925
4	1e+12	NDD	93.195	93.202	0.0074
5	5e+12	NDD	90.313	90.565	0.2518
6	5e+12	NDD	92.676	92.754	0.0778
7	5e+12	NDD	91.779	91.735	-0.0434
8	5e+12	NDD	92.988	93.297	0.3089
9	1e+13	NDD	91.043	90.926	-0.1171
10	1e+13	NDD	94.498	94.025	-0.4724
11	1e+13	NDD	94.87	94.572	-0.2977
12	1e+13	NDD	94.187	93.911	-0.2759
91	0	CORRELATION	93.904	93.958	0.0543
92	0	CORRELATION	94.483	94.511	0.0279
93	0	CORRELATION	92.969	92.955	-0.014
94	0	CORRELATION	94.546	94.564	0.018
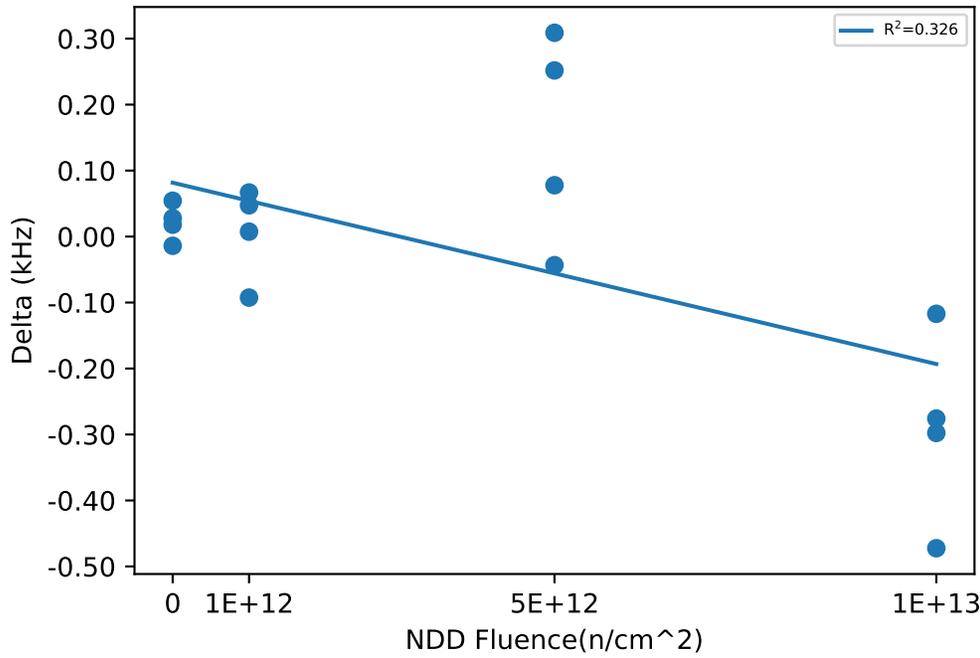
Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	92.969	93.975	94.546	0.73064	92.955	93.997	94.564	0.7468	-0.014	0.02155	0.0543	0.028221
1e+12	92.875	93.453	94.056	0.52263	92.942	93.461	94.104	0.50576	-0.0925	0.007275	0.0668	0.070966
5e+12	90.313	91.939	92.988	1.199	90.565	92.088	93.297	1.204	-0.0434	0.14878	0.3089	0.16148
1e+13	91.043	93.65	94.87	1.7597	90.926	93.359	94.572	1.6471	-0.4724	-0.29078	-0.1171	0.1454
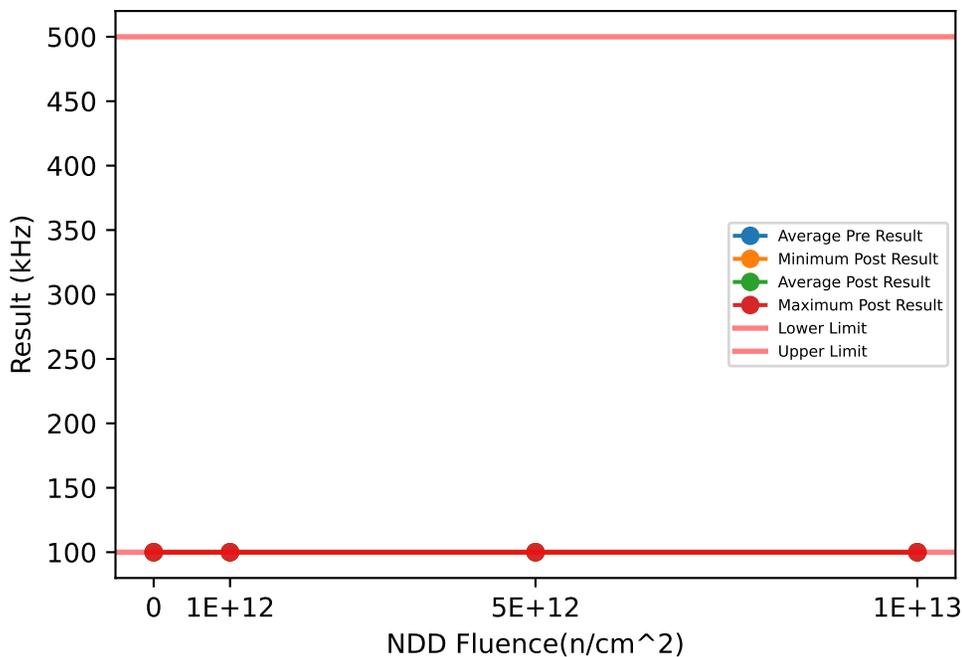
Device Test: 20.50 LEVEL|FREQ/SYNC/14/14/0/1000/5/100kHz//@FREQ_SYNC_EXT_503X

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 100.0, Upper Limit = 500.0 (kHz))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	99.957	99.999	0.0415
2	1e+12	NDD	99.993	100	0.0083
3	1e+12	NDD	99.992	99.999	0.0074
4	1e+12	NDD	99.994	100	0.0069
5	5e+12	NDD	99.999	100	0.0013
6	5e+12	NDD	99.994	100	0.0074
7	5e+12	NDD	99.993	100	0.0085
8	5e+12	NDD	99.995	100	0.0055
9	1e+13	NDD	99.996	100	0.0053
10	1e+13	NDD	99.995	100	0.0067
11	1e+13	NDD	99.992	99.999	0.0078
12	1e+13	NDD	99.995	100	0.0056
91	0	CORRELATION	99.995	100	0.006
92	0	CORRELATION	99.993	100	0.0071
93	0	CORRELATION	99.993	100	0.0068
94	0	CORRELATION	99.995	99.998	0.003
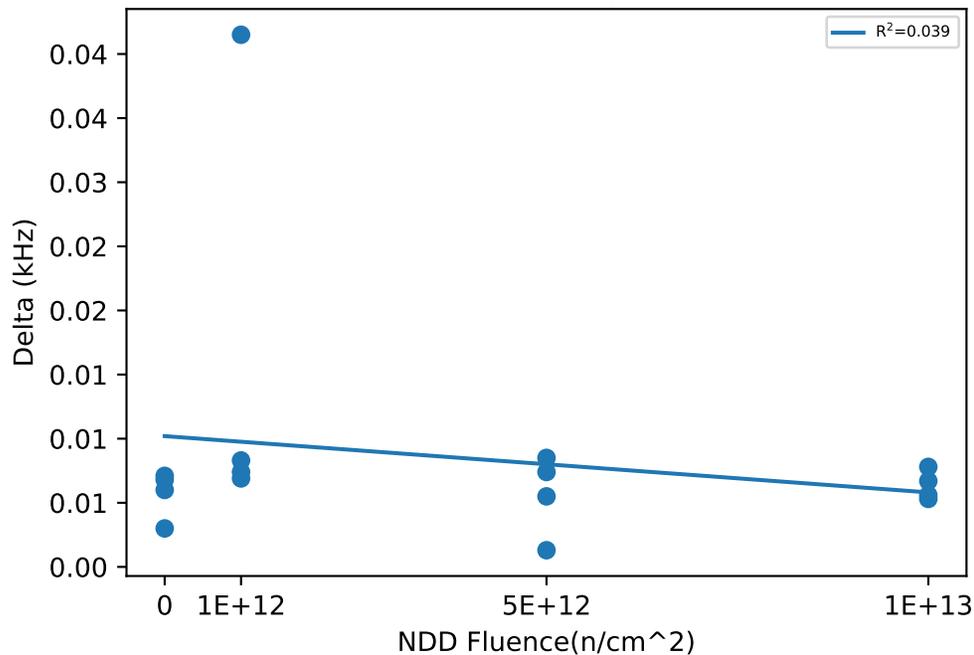
Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	99.993	99.994	99.995	0.0011705	99.998	100	100	0.00096047	0.003	0.005725	0.0071	0.0018751
1e+12	99.957	99.984	99.994	0.017702	99.999	100	100	0.0011269	0.0069	0.016025	0.0415	0.016993
5e+12	99.993	99.995	99.999	0.0027628	100	100	100	0.00043493	0.0013	0.005675	0.0085	0.003169
1e+13	99.992	99.994	99.996	0.0018392	99.999	100	100	0.00084212	0.0053	0.00635	0.0078	0.0011387
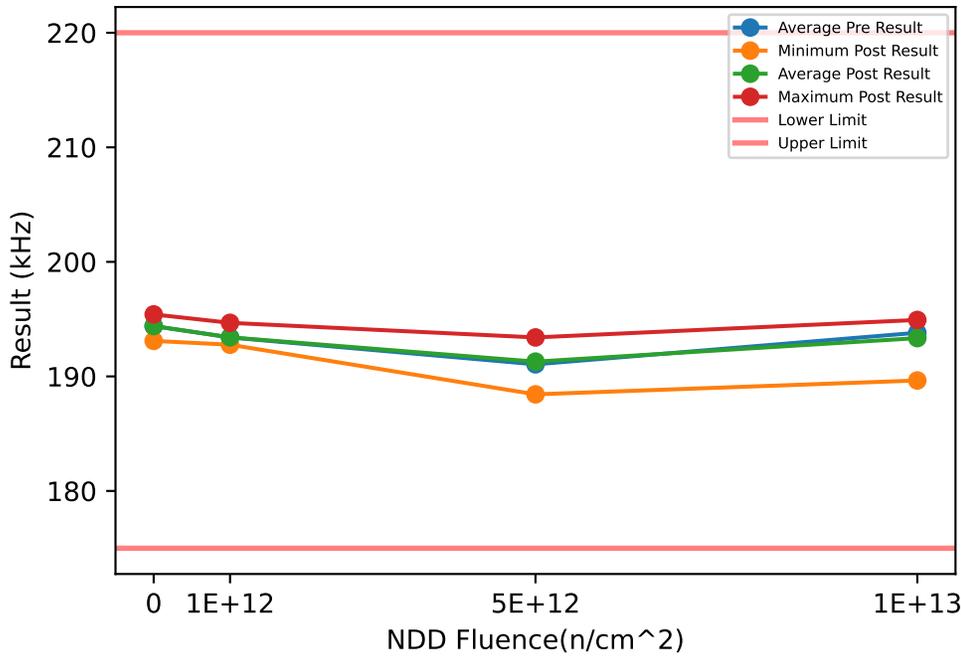
Device Test: 20.51 LEVEL|FREQ/RT/12/12/0/1000/5/200kHz//@FSW_EXT_RT_B

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 175.0, Upper Limit = 220.0 (kHz))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	192.86	192.99	0.1277
2	1e+12	NDD	194.58	194.68	0.0926
3	1e+12	NDD	193.39	193.22	-0.1735
4	1e+12	NDD	192.78	192.77	-0.0087
5	5e+12	NDD	188.08	188.43	0.3552
6	5e+12	NDD	192.25	192.38	0.1348
7	5e+12	NDD	190.94	190.94	-0.0006
8	5e+12	NDD	192.95	193.4	0.4496
9	1e+13	NDD	189.89	189.64	-0.249
10	1e+13	NDD	195.01	194.27	-0.732
11	1e+13	NDD	195.4	194.93	-0.4713
12	1e+13	NDD	194.95	194.53	-0.4162
91	0	CORRELATION	193.71	193.73	0.0245
92	0	CORRELATION	195.31	195.31	0.0003
93	0	CORRELATION	193.12	193.1	-0.023
94	0	CORRELATION	195.45	195.41	-0.039
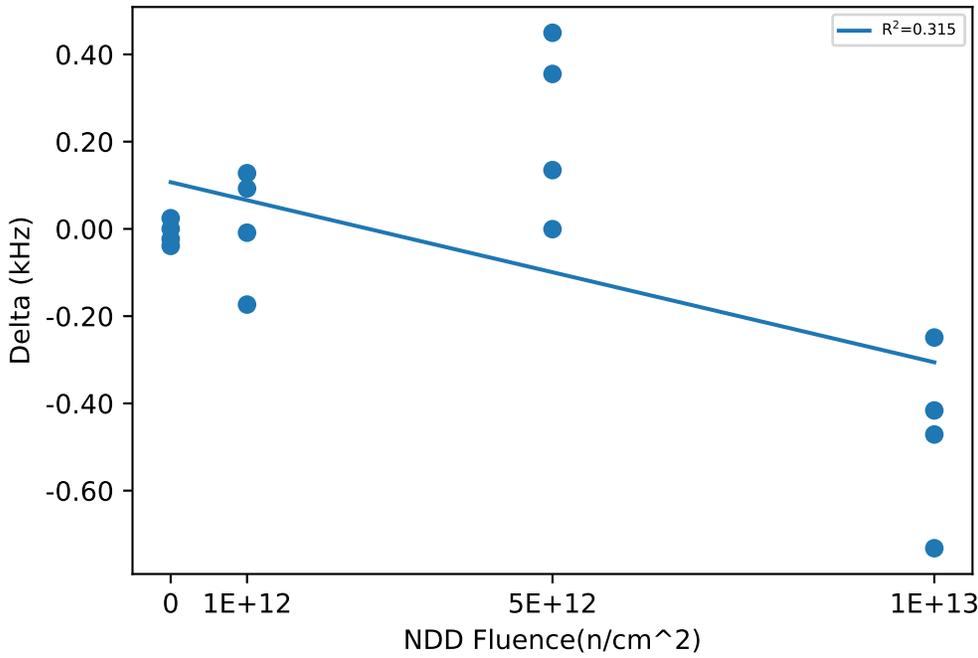
Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	193.12	194.4	195.45	1.1618	193.1	194.39	195.41	1.1539	-0.039	-0.0093	0.0245	0.027715
1e+12	192.78	193.4	194.58	0.83371	192.77	193.41	194.68	0.86312	-0.1735	0.009525	0.1277	0.13503
5e+12	188.08	191.05	192.95	2.1518	188.43	191.29	193.4	2.155	-0.0006	0.23475	0.4496	0.20498
1e+13	189.89	193.81	195.4	2.6194	189.64	193.34	194.93	2.4809	-0.732	-0.46713	-0.249	0.20029
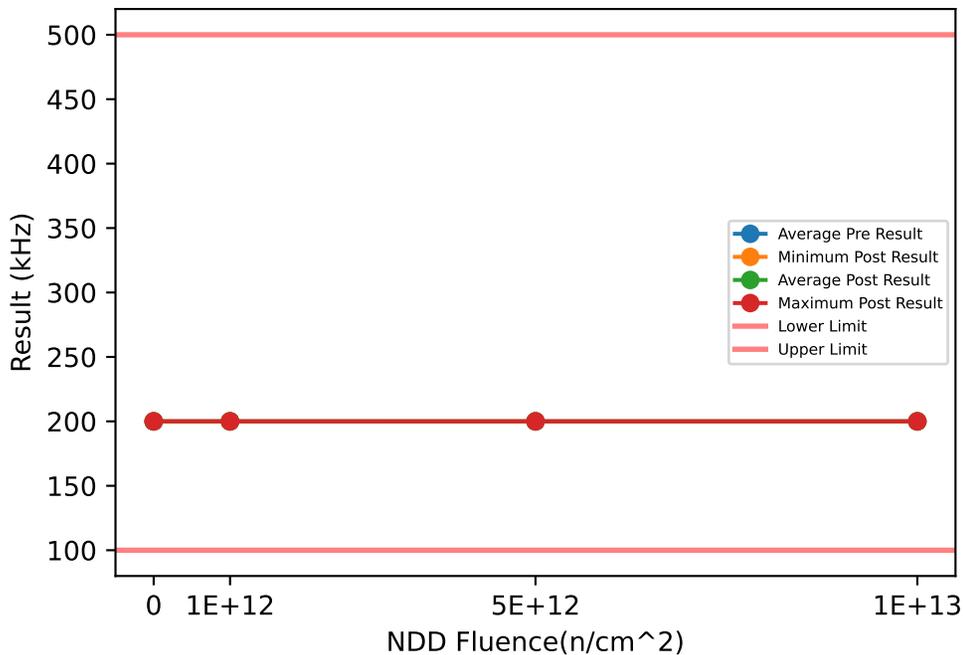
Device Test: 20.52 LEVEL|FREQ/SYNC/12/12/0/1000/5/200kHz//@FREQ_SYNC_EXT_503X

## NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 100.0, Upper Limit = 500.0 (kHz))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	199.99	200	0.0075
2	1e+12	NDD	199.98	200	0.0255
3	1e+12	NDD	199.97	200	0.0352
4	1e+12	NDD	199.98	200	0.0206
5	5e+12	NDD	199.99	200	0.0087
6	5e+12	NDD	199.98	200	0.0284
7	5e+12	NDD	199.97	200	0.033
8	5e+12	NDD	199.98	200	0.0183
9	1e+13	NDD	199.98	200	0.0136
10	1e+13	NDD	199.97	200	0.0337
11	1e+13	NDD	199.97	200	0.0376
12	1e+13	NDD	199.97	200	0.0284
91	0	CORRELATION	199.99	199.99	0.0021
92	0	CORRELATION	199.98	200	0.024
93	0	CORRELATION	199.98	200	0.0217
94	0	CORRELATION	199.98	200	0.022
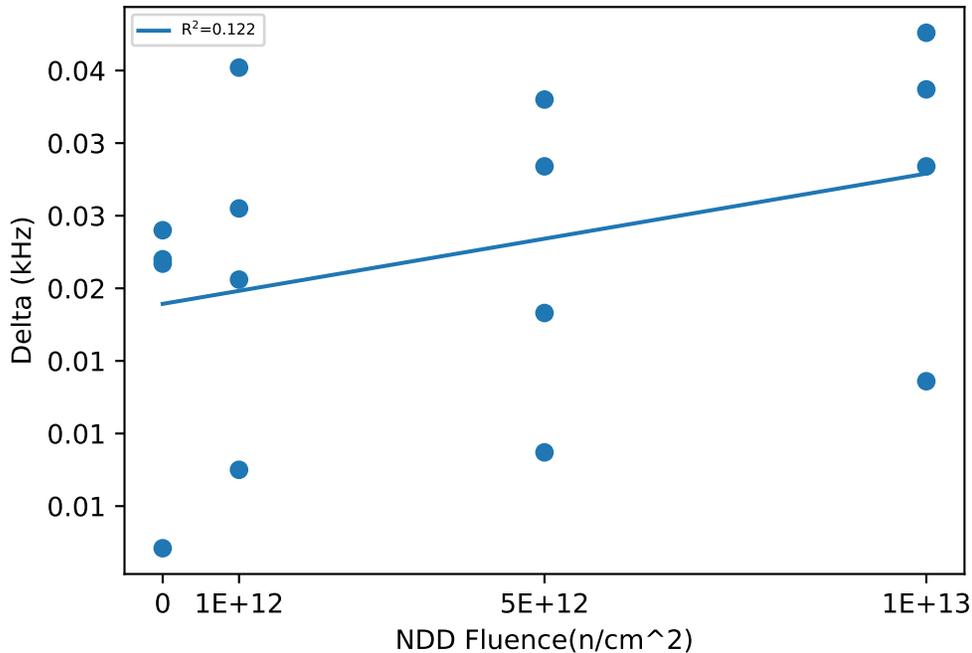
Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	199.98	199.98	199.99	0.0064211	199.99	200	200	0.0053914	0.0021	0.01745	0.024	0.010284
1e+12	199.97	199.98	199.99	0.0083978	200	200	200	0.0041065	0.0075	0.0222	0.0352	0.011526
5e+12	199.97	199.98	199.99	0.010174	200	200	200	0.0019536	0.0087	0.0221	0.033	0.01084
1e+13	199.97	199.97	199.98	0.0072367	200	200	200	0.0034881	0.0136	0.028325	0.0376	0.010516
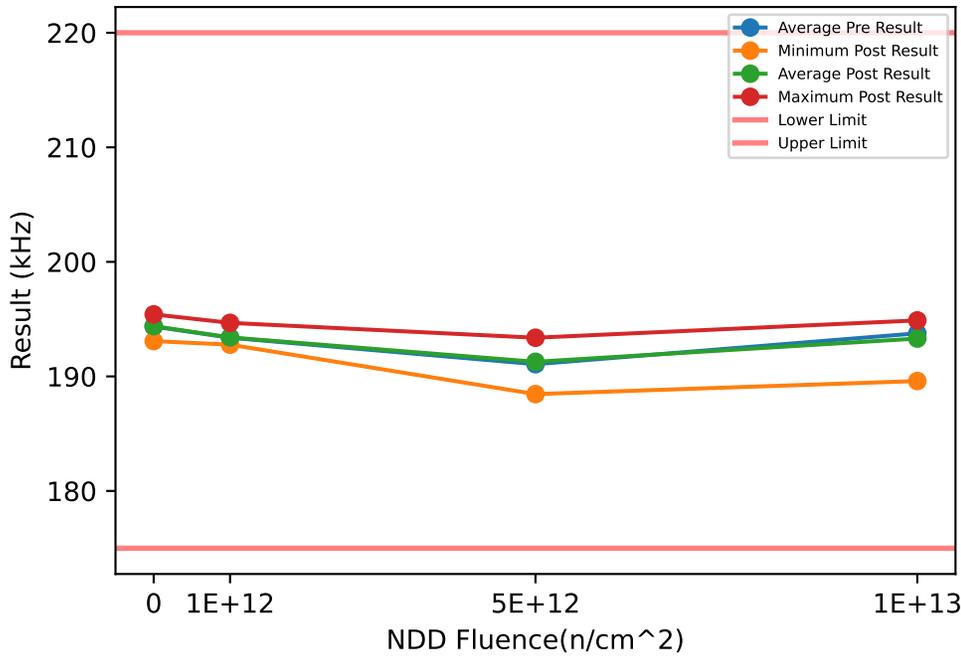
Device Test: 20.53 LEVEL|FREQ/RT/14/14/0/1000/5/200kHz//@FSW_EXT_RT_B

NDD vs Result Stats

Legend: Average Pre Result, Minimum Post Result, Average Post Result, Maximum Post Result, Lower Limit, Upper Limit

NDD vs Post - Pre Exposure Delta

R²=0.385

Test Results (Lower Limit = 175.0, Upper Limit = 220.0 (kHz))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	192.84	192.95	0.1162
2	1e+12	NDD	194.58	194.67	0.0929
3	1e+12	NDD	193.37	193.22	-0.1426
4	1e+12	NDD	192.73	192.77	0.0444
5	5e+12	NDD	188.09	188.45	0.3691
6	5e+12	NDD	192.26	192.35	0.0895
7	5e+12	NDD	190.94	190.92	-0.0143
8	5e+12	NDD	192.99	193.38	0.388
9	1e+13	NDD	189.83	189.6	-0.2363
10	1e+13	NDD	194.97	194.25	-0.7195
11	1e+13	NDD	195.35	194.89	-0.4608
12	1e+13	NDD	194.89	194.48	-0.41
91	0	CORRELATION	193.67	193.73	0.0584
92	0	CORRELATION	195.26	195.32	0.0644
93	0	CORRELATION	193.1	193.08	-0.0137
94	0	CORRELATION	195.39	195.42	0.0235
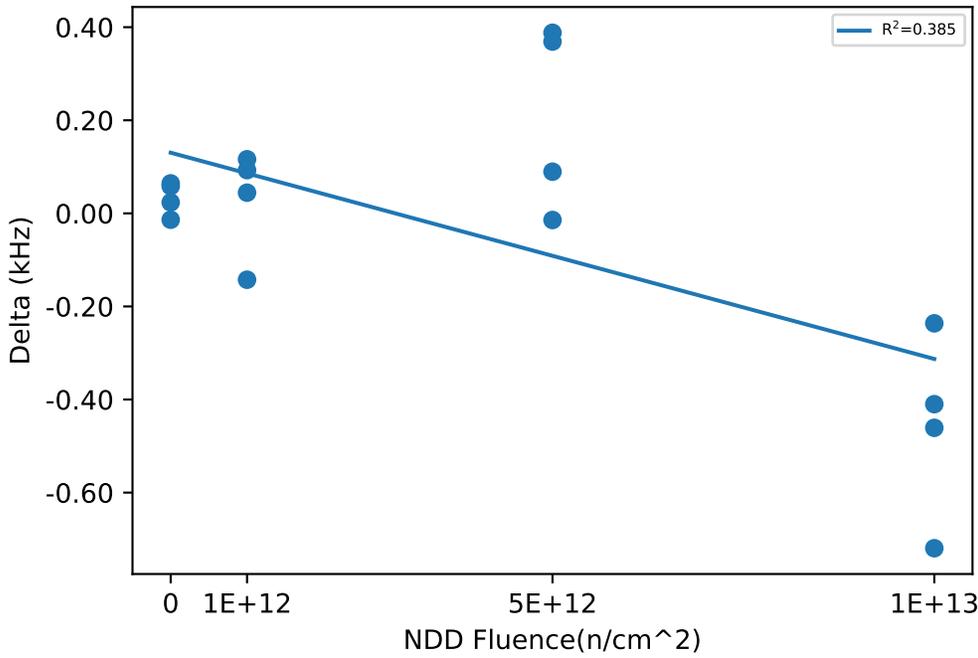
Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	193.1	194.35	195.39	1.1473	193.08	194.39	195.42	1.1651	-0.0137	0.03315	0.0644	0.036066
1e+12	192.73	193.38	194.58	0.84906	192.77	193.41	194.67	0.86563	-0.1426	0.027725	0.1162	0.11742
5e+12	188.09	191.07	192.99	2.1615	188.45	191.27	193.38	2.1327	-0.0143	0.20808	0.388	0.2015
1e+13	189.83	193.76	195.35	2.6268	189.6	193.3	194.89	2.4864	-0.7195	-0.45665	-0.2363	0.19986
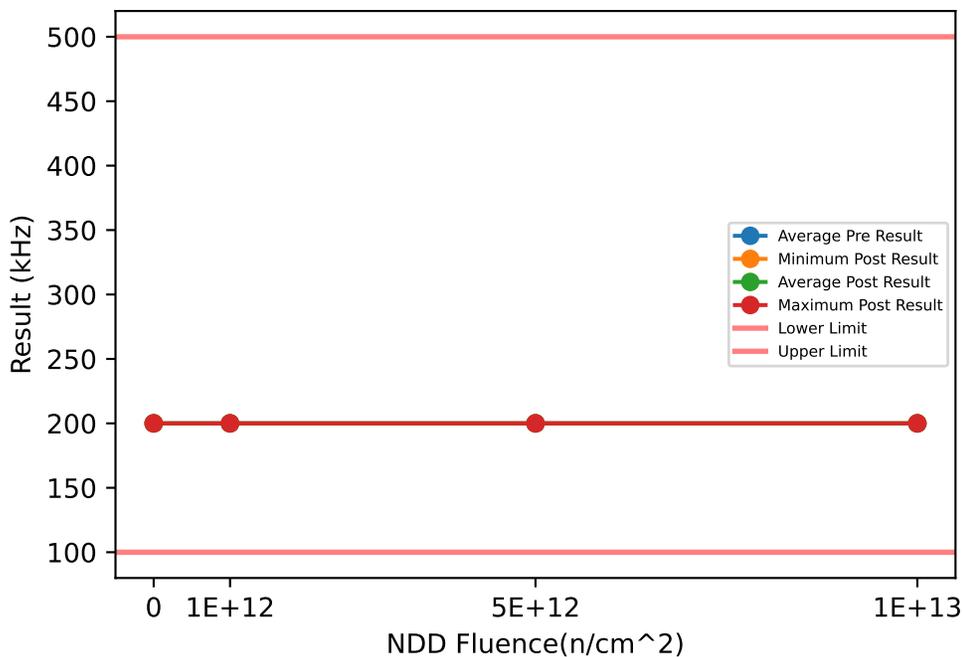
Device Test: 20.54 LEVEL|FREQ/SYNC/14/14/0/1000/5/200kHz//@FREQ_SYNC_EXT_503X

## NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 100.0, Upper Limit = 500.0 (kHz))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	199.98	200	0.0217
2	1e+12	NDD	199.97	200	0.0333
3	1e+12	NDD	199.97	200.01	0.0326
4	1e+12	NDD	199.98	200	0.0188
5	5e+12	NDD	199.99	200	0.0089
6	5e+12	NDD	199.97	200	0.0231
7	5e+12	NDD	199.97	200	0.0265
8	5e+12	NDD	199.98	200	0.0216
9	1e+13	NDD	199.99	200	0.0096
10	1e+13	NDD	199.98	200	0.0246
11	1e+13	NDD	199.97	200	0.0245
12	1e+13	NDD	199.98	200	0.0206
91	0	CORRELATION	199.98	200	0.0168
92	0	CORRELATION	199.97	200.01	0.0367
93	0	CORRELATION	199.97	200	0.0298
94	0	CORRELATION	199.98	200	0.0231
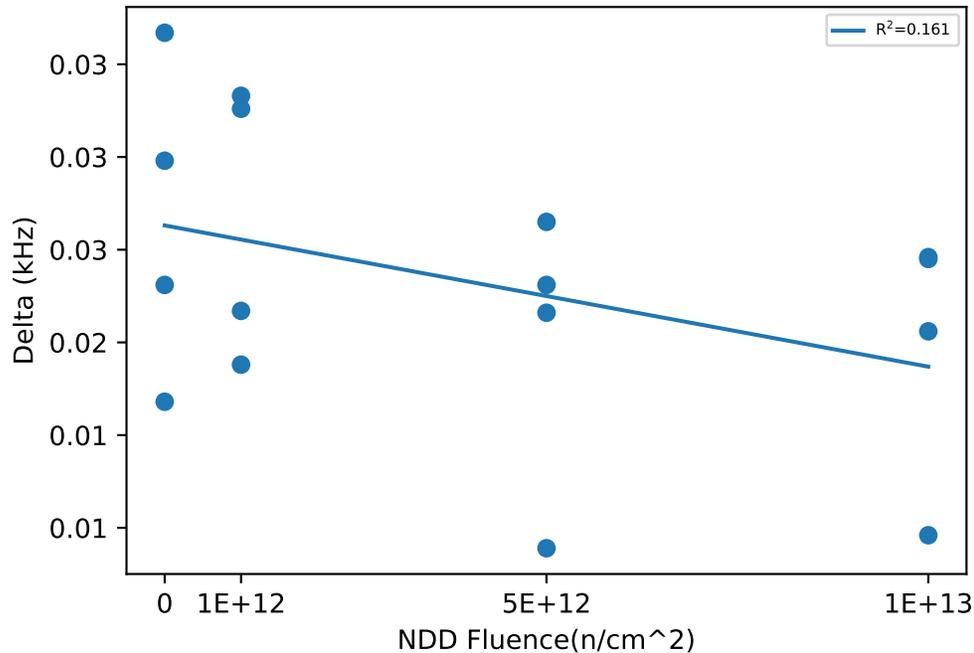
Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	199.97	199.98	199.98	0.0057297	200	200	200.01	0.0036263	0.0168	0.0266	0.0367	0.008574
1e+12	199.97	199.98	199.98	0.00394	200	200	200.01	0.0042352	0.0188	0.0266	0.0333	0.0074328
5e+12	199.97	199.98	199.99	0.0073686	200	200	200	0.0030137	0.0089	0.020025	0.0265	0.0076947
1e+13	199.97	199.98	199.99	0.0062809	200	200	200	0.0021917	0.0096	0.019825	0.0246	0.0070665
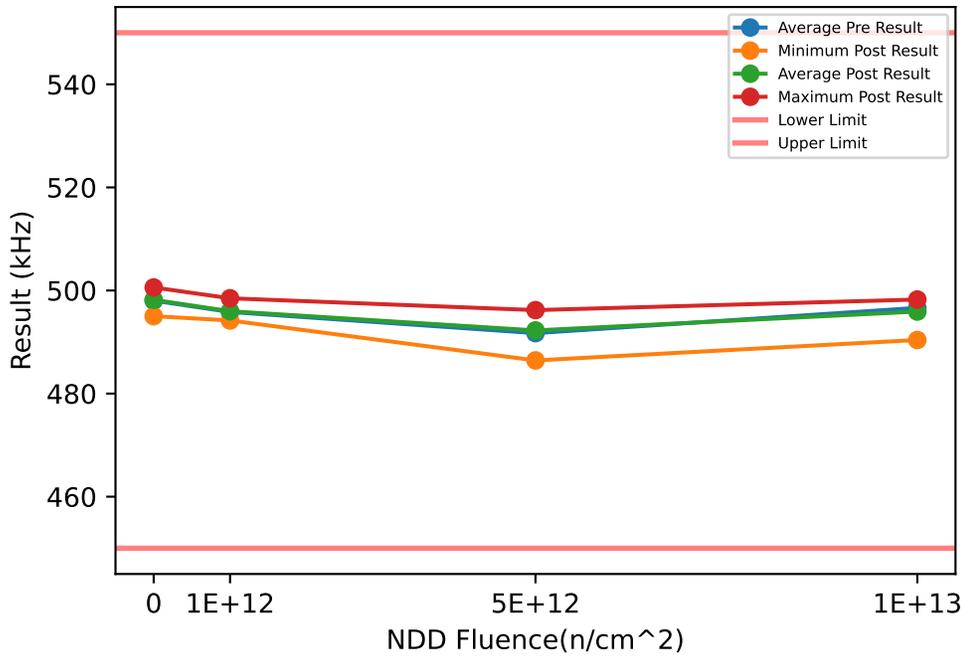
Device Test: 20.55 LEVEL|FREQ/RT/12/12/0/1000/5/500kHz//@FSW_EXT_RT_C

NDD vs Result Stats

Legend: Average Pre Result, Minimum Post Result, Average Post Result, Maximum Post Result, Lower Limit, Upper Limit

Y-axis: Result (kHz); X-axis: NDD Fluence(n/cm^2)

NDD vs Post - Pre Exposure Delta

Legend: R^2=0.399

Y-axis: Delta (kHz); X-axis: NDD Fluence(n/cm^2)

## Test Results (Lower Limit = 450.0, Upper Limit = 550.0 (kHz))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	496.22	496.51	0.2834
2	1e+12	NDD	498.21	498.49	0.2757
3	1e+12	NDD	494.88	494.74	-0.139
4	1e+12	NDD	494	494.19	0.183
5	5e+12	NDD	485.81	486.43	0.6196
6	5e+12	NDD	493.68	494.03	0.3572
7	5e+12	NDD	492.04	492.35	0.3087
8	5e+12	NDD	495.37	496.19	0.8267
9	1e+13	NDD	490.98	490.4	-0.5848
10	1e+13	NDD	498.29	497.21	-1.0804
11	1e+13	NDD	498.47	497.82	-0.6545
12	1e+13	NDD	498.78	498.24	-0.5333
91	0	CORRELATION	494.81	495.02	0.215
92	0	CORRELATION	499.79	500	0.2087
93	0	CORRELATION	497.05	497.18	0.1255
94	0	CORRELATION	500.48	500.59	0.1113
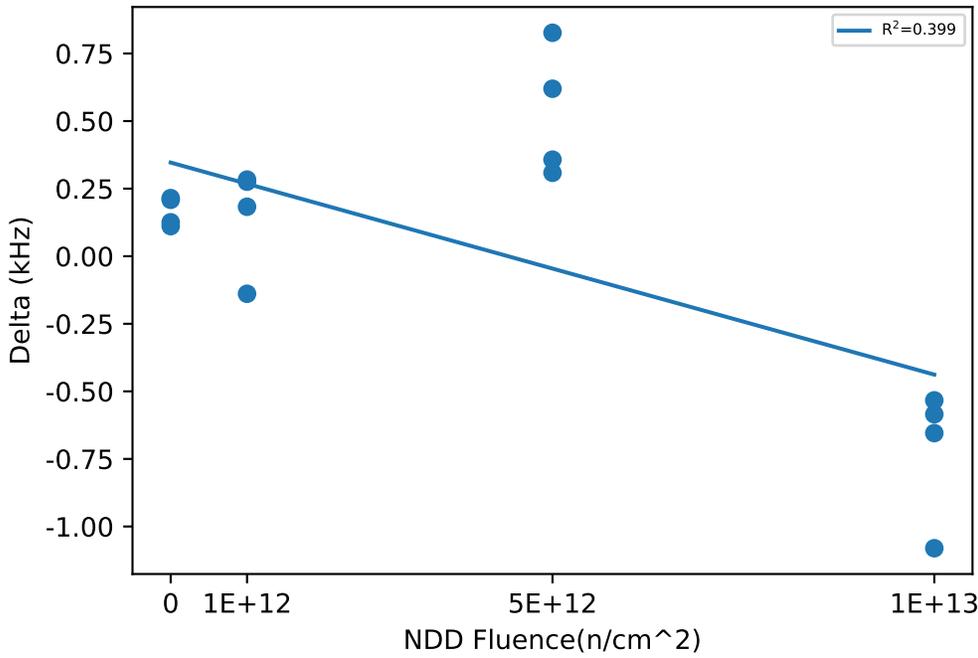
Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	494.81	498.03	500.48	2.6109	495.02	498.2	500.59	2.5888	0.1113	0.16512	0.215	0.054325
1e+12	494	495.83	498.21	1.8333	494.19	495.98	498.49	1.9438	-0.139	0.15078	0.2834	0.1985
5e+12	485.81	491.73	495.37	4.1673	486.43	492.25	496.19	4.1857	0.3087	0.52805	0.8267	0.24144
1e+13	490.98	496.63	498.78	3.7708	490.4	495.92	498.24	3.7042	-1.0804	-0.71325	-0.5333	0.24975
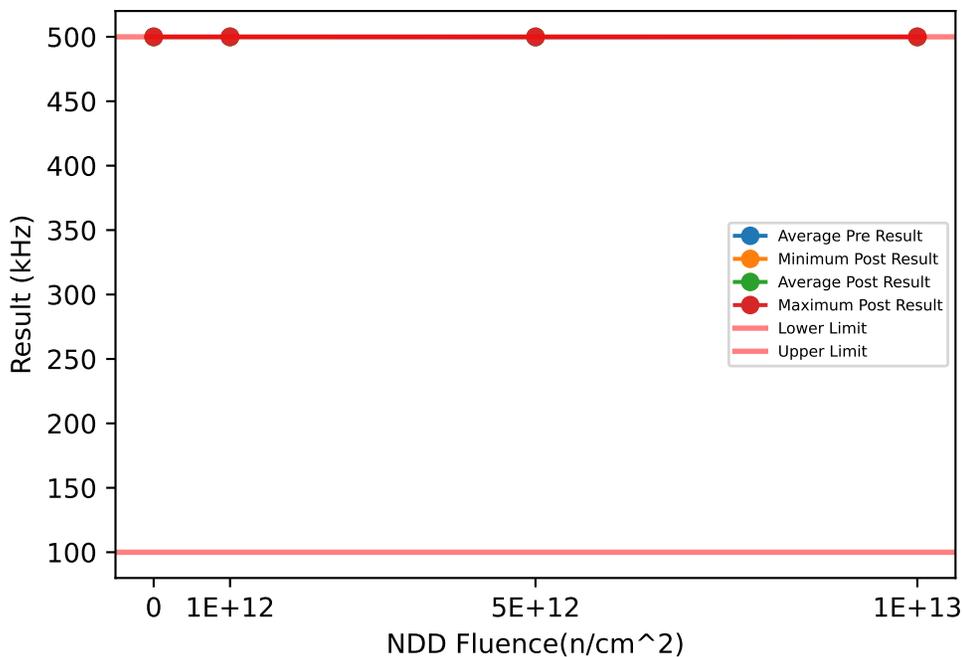
Device Test: 20.56 LEVEL|FREQ/SYNC/12/12/0/1000/5/500kHz//@FREQ_SYNC_EXT_503X

## NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 100.0, Upper Limit = 500.0 (kHz))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	499.84	499.97	0.123
2	1e+12	NDD	499.86	500.03	0.179
3	1e+12	NDD	499.83	499.98	0.1413
4	1e+12	NDD	499.88	499.98	0.1031
5	5e+12	NDD	499.41	499.97	0.562
6	5e+12	NDD	499.82	499.99	0.1783
7	5e+12	NDD	499.83	500.01	0.1799
8	5e+12	NDD	499.88	499.99	0.1151
9	1e+13	NDD	499.86	499.96	0.096
10	1e+13	NDD	499.86	500.01	0.1445
11	1e+13	NDD	499.83	500.03	0.1969
12	1e+13	NDD	499.88	500	0.1216
91	0	CORRELATION	499.86	499.95	0.0856
92	0	CORRELATION	499.83	500.01	0.1825
93	0	CORRELATION	499.81	499.98	0.1705
94	0	CORRELATION	499.85	500	0.1462
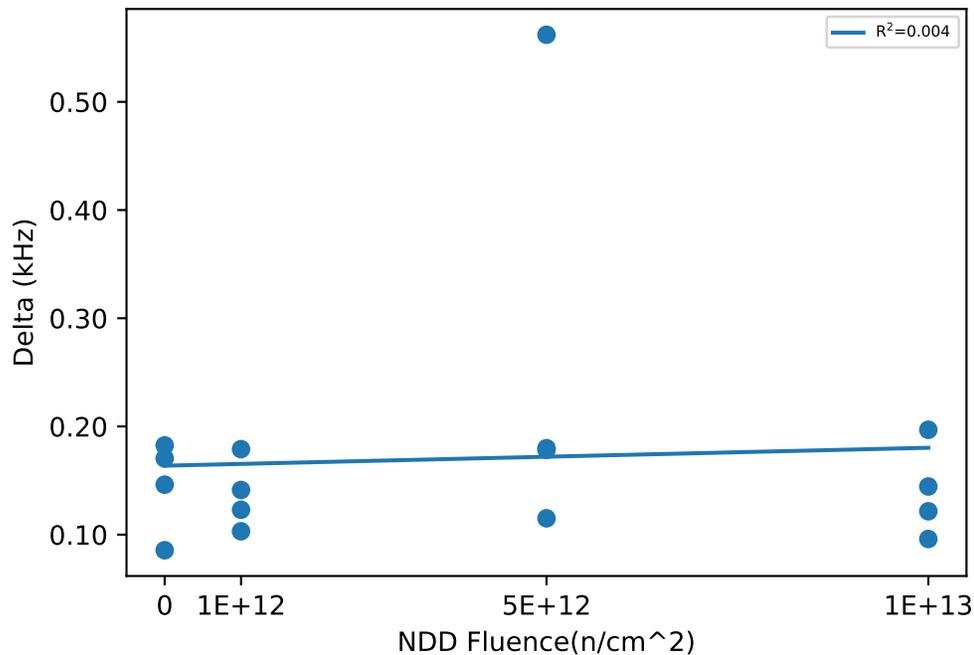
Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	499.81	499.84	499.86	0.023922	499.95	499.98	500.01	0.026474	0.0856	0.1462	0.1825	0.04313
1e+12	499.83	499.85	499.88	0.018684	499.97	499.99	500.03	0.03088	0.1031	0.1366	0.179	0.032285
5e+12	499.41	499.73	499.88	0.21767	499.97	499.99	500.01	0.014987	0.1151	0.25882	0.562	0.20436
1e+13	499.83	499.86	499.88	0.021988	499.96	500	500.03	0.028564	0.096	0.13975	0.1969	0.042942
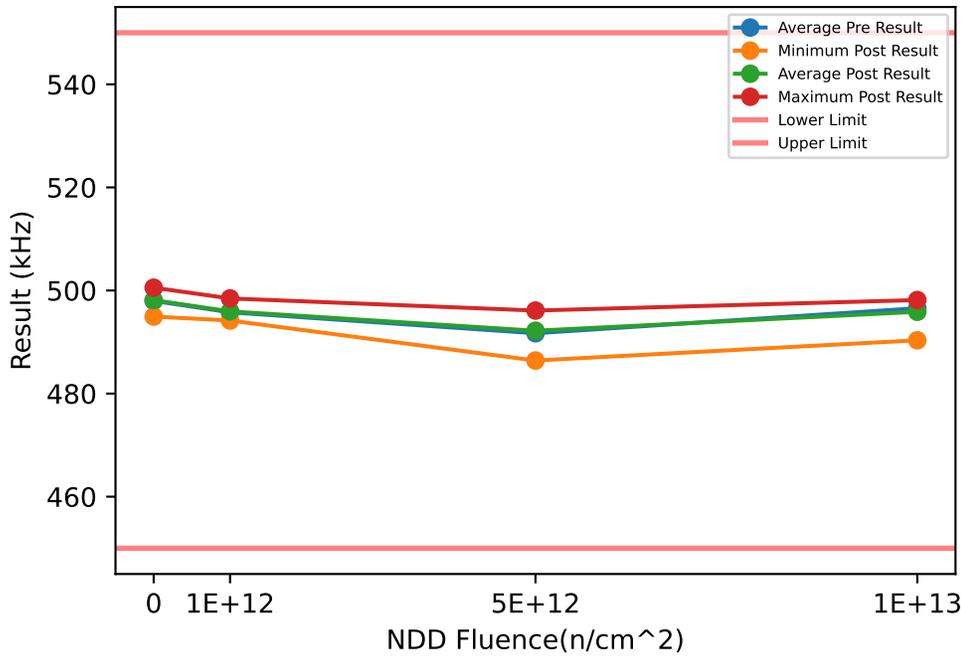
Device Test: 20.57 LEVEL|FREQ/RT/14/14/0/1000/5/500kHz//@FSW_EXT_RT_C

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 450.0, Upper Limit = 550.0 (kHz))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	496.1	496.45	0.3498
2	1e+12	NDD	498.18	498.46	0.281
3	1e+12	NDD	494.84	494.7	-0.1487
4	1e+12	NDD	493.94	494.18	0.2352
5	5e+12	NDD	485.79	486.41	0.6241
6	5e+12	NDD	493.69	493.94	0.2506
7	5e+12	NDD	492.04	492.31	0.2763
8	5e+12	NDD	495.3	496.11	0.8081
9	1e+13	NDD	490.93	490.34	-0.5869
10	1e+13	NDD	498.21	497.16	-1.049
11	1e+13	NDD	498.44	497.83	-0.615
12	1e+13	NDD	498.67	498.14	-0.5267
91	0	CORRELATION	494.78	494.94	0.1661
92	0	CORRELATION	499.68	499.94	0.2562
93	0	CORRELATION	496.99	497.1	0.1054
94	0	CORRELATION	500.45	500.54	0.0876
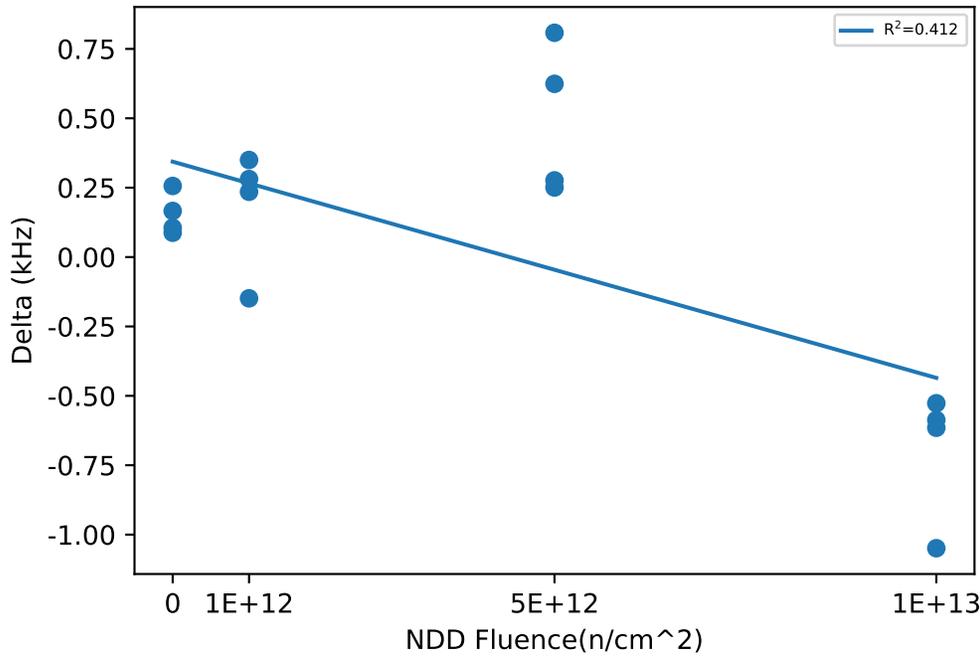
Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	494.78	497.98	500.45	2.5961	494.94	498.13	500.54	2.5996	0.0876	0.15382	0.2562	0.076075
1e+12	493.94	495.77	498.18	1.8373	494.18	495.95	498.46	1.9394	-0.1487	0.17933	0.3498	0.2237
5e+12	485.79	491.7	495.3	4.1613	486.41	492.19	496.11	4.1545	0.2506	0.48977	0.8081	0.27212
1e+13	490.93	496.56	498.67	3.7617	490.34	495.87	498.14	3.7082	-1.049	-0.6944	-0.5267	0.23925
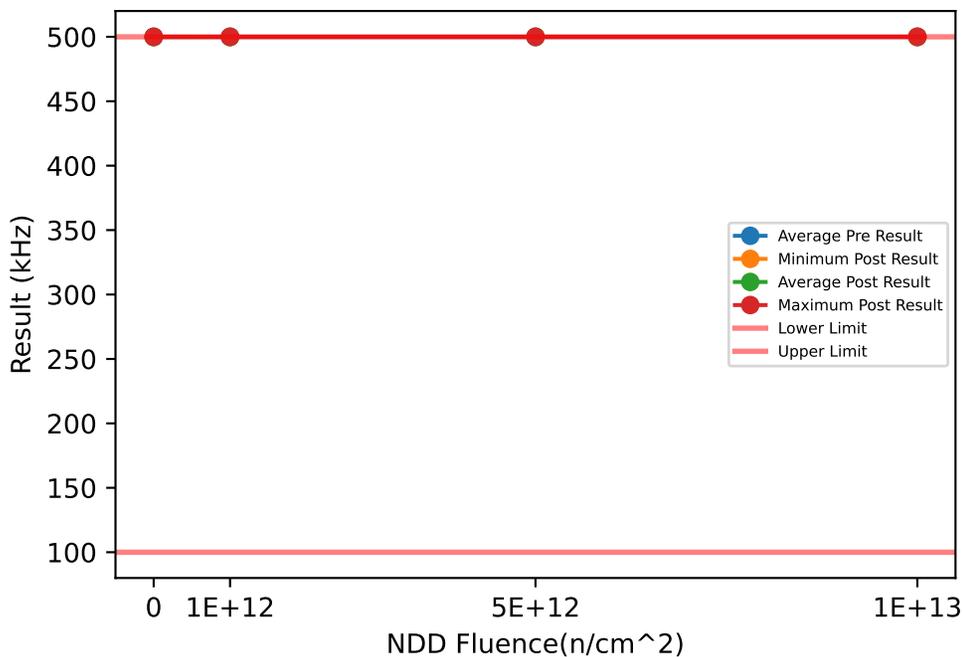
Device Test: 20.58 LEVEL|FREQ/SYNC/14/14/0/1000/5/500kHz//@FREQ_SYNC_EXT_503X

NDD vs Result Stats

Legend:
- Average Pre Result
- Minimum Post Result
- Average Post Result
- Maximum Post Result
- Lower Limit
- Upper Limit

NDD vs Post - Pre Exposure Delta

R²=0.003

Test Results (Lower Limit = 100.0, Upper Limit = 500.0 (kHz))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	499.94	500	0.0635
2	1e+12	NDD	499.86	499.98	0.1265
3	1e+12	NDD	499.84	500.03	0.1915
4	1e+12	NDD	499.89	499.99	0.0996
5	5e+12	NDD	499.95	500	0.0457
6	5e+12	NDD	499.84	500.03	0.1901
7	5e+12	NDD	499.84	500.02	0.1795
8	5e+12	NDD	499.88	500.03	0.1468
9	1e+13	NDD	500	500.01	0.007
10	1e+13	NDD	499.87	500	0.1301
11	1e+13	NDD	499.8	500	0.1997
12	1e+13	NDD	499.88	500.03	0.1504
91	0	CORRELATION	499.95	499.96	0.0081
92	0	CORRELATION	499.85	500.01	0.1553
93	0	CORRELATION	499.85	500.02	0.1654
94	0	CORRELATION	499.84	499.98	0.1337
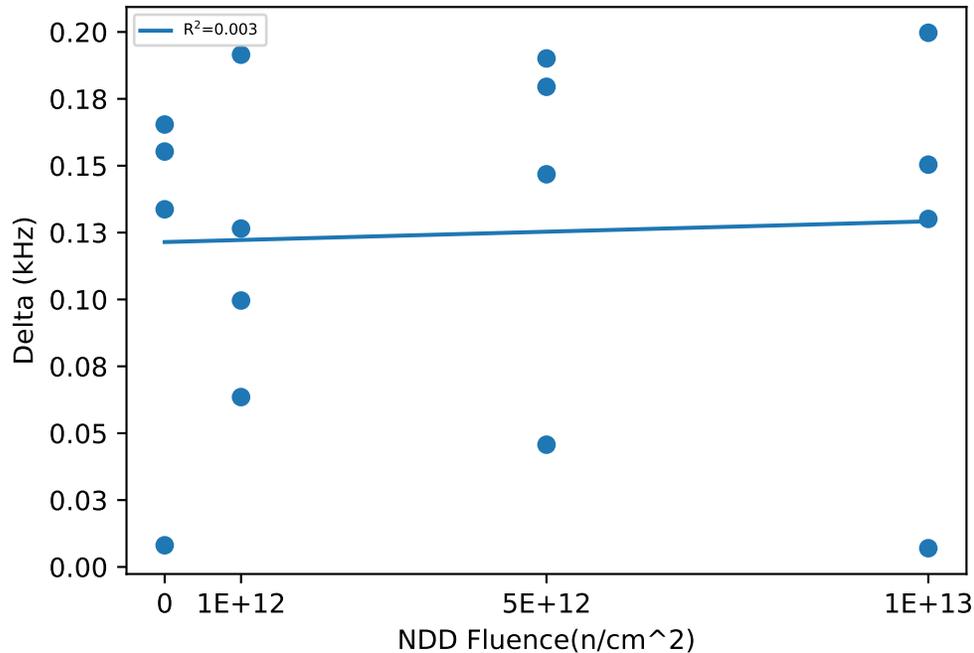
Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	499.84	499.87	499.95	0.049721	499.96	499.99	500.02	0.028991	0.0081	0.11562	0.1654	0.072893
1e+12	499.84	499.88	499.94	0.044143	499.98	500	500.03	0.021268	0.0635	0.12027	0.1915	0.054045
5e+12	499.84	499.88	499.95	0.055375	500	500.02	500.03	0.012424	0.0457	0.14052	0.1901	0.065848
1e+13	499.8	499.89	500	0.082591	500	500.01	500.03	0.015395	0.007	0.1218	0.1997	0.081923

Device Test: 20.72 FREQ|DETECTION/SYNC/12/12/0/0/5/100kHz//@T_SYNC_DET

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta
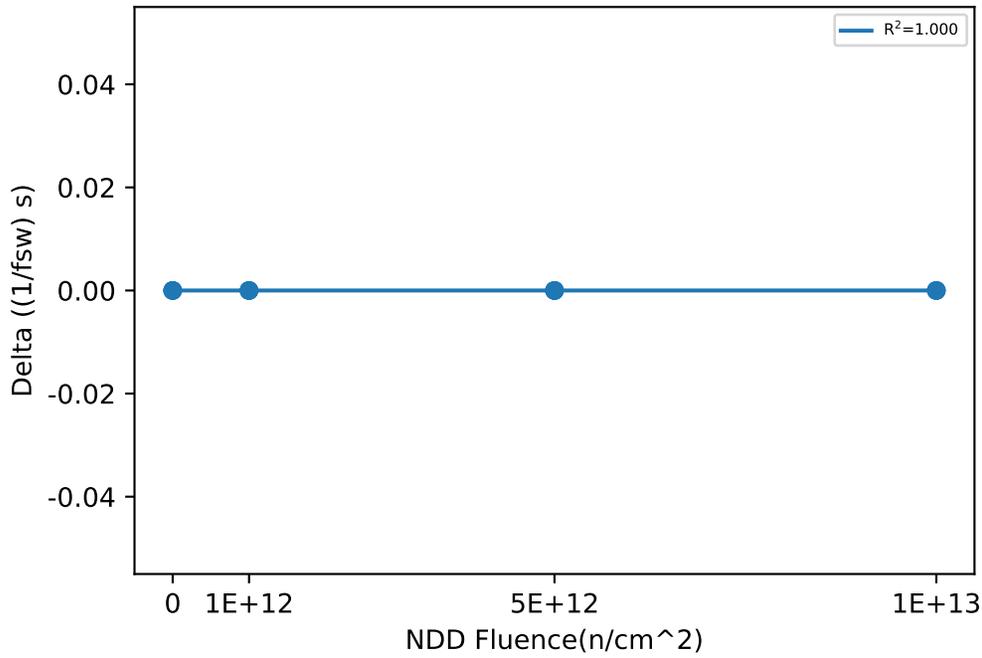

Test Results (Upper Limit = 5.0 ((1/fsw) s))

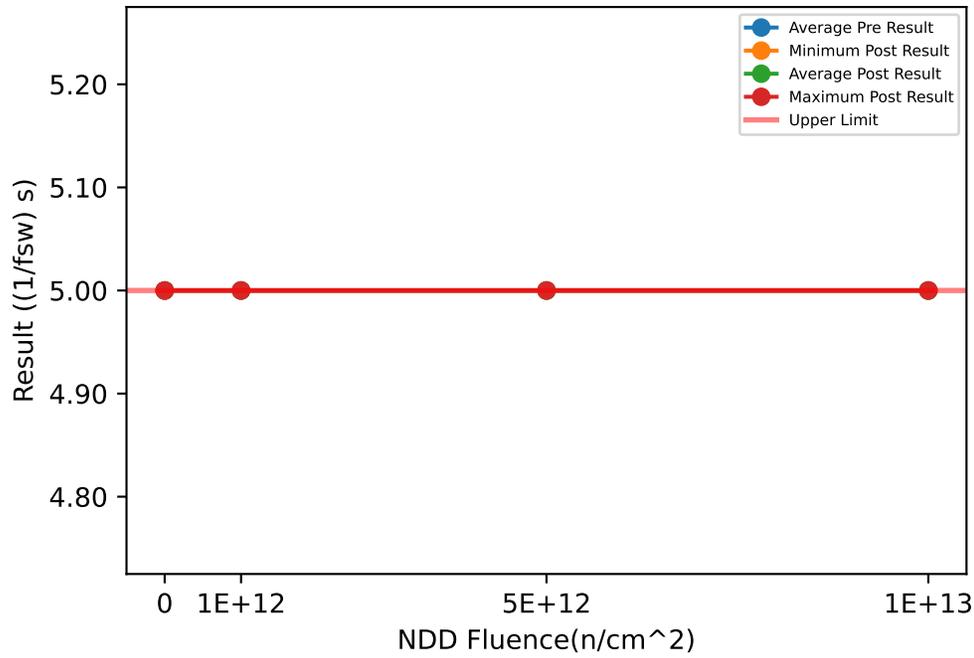| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	5	5	0
2	1e+12	NDD	5	5	0
3	1e+12	NDD	5	5	0
4	1e+12	NDD	5	5	0
5	5e+12	NDD	5	5	0
6	5e+12	NDD	5	5	0
7	5e+12	NDD	5	5	0
8	5e+12	NDD	5	5	0
9	1e+13	NDD	5	5	0
10	1e+13	NDD	5	5	0
11	1e+13	NDD	5	5	0
12	1e+13	NDD	5	5	0
91	0	CORRELATION	5	5	0
92	0	CORRELATION	5	5	0
93	0	CORRELATION	5	5	0
94	0	CORRELATION	5	5	0

Test Statistics ((1/fsw) s)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5	5	5	0	5	5	5	0	0	0	0	0
1e+12	5	5	5	0	5	5	5	0	0	0	0	0
5e+12	5	5	5	0	5	5	5	0	0	0	0	0
1e+13	5	5	5	0	5	5	5	0	0	0	0	0

Device Test: 20.74 FREQ|DETECTION/SYNC/14/14/0/0/5/100kHz//@T_SYNC_DET

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 5.0 ((1/fsw) s))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	5	5	0
2	1e+12	NDD	5	5	0
3	1e+12	NDD	5	5	0
4	1e+12	NDD	5	5	0
5	5e+12	NDD	5	5	0
6	5e+12	NDD	5	5	0
7	5e+12	NDD	5	5	0
8	5e+12	NDD	5	5	0
9	1e+13	NDD	5	5	0
10	1e+13	NDD	5	5	0
11	1e+13	NDD	5	5	0
12	1e+13	NDD	5	5	0
91	0	CORRELATION	5	5	0
92	0	CORRELATION	5	5	0
93	0	CORRELATION	5	5	0
94	0	CORRELATION	5	5	0

Test Statistics ((1/fsw) s)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5	5	5	0	5	5	5	0	0	0	0	0
1e+12	5	5	5	0	5	5	5	0	0	0	0	0
5e+12	5	5	5	0	5	5	5	0	0	0	0	0
1e+13	5	5	5	0	5	5	5	0	0	0	0	0

Device Test: 20.76 FREQ|DETECTION/SYNC/12/12/0/0/5/200kHz//@T_SYNC_DET

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta
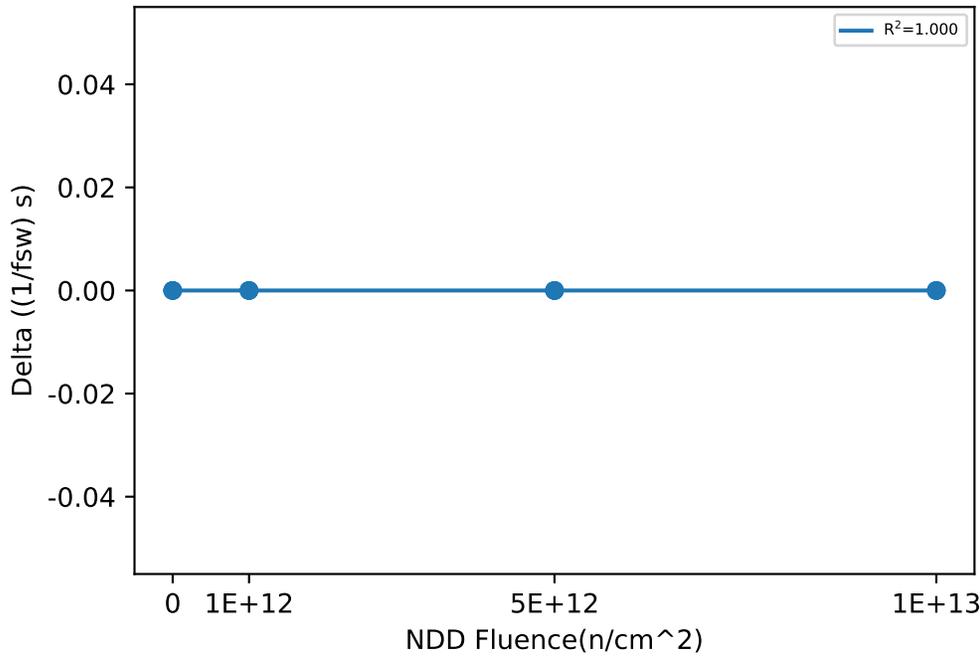

Test Results (Upper Limit = 5.0 ((1/fsw) s))

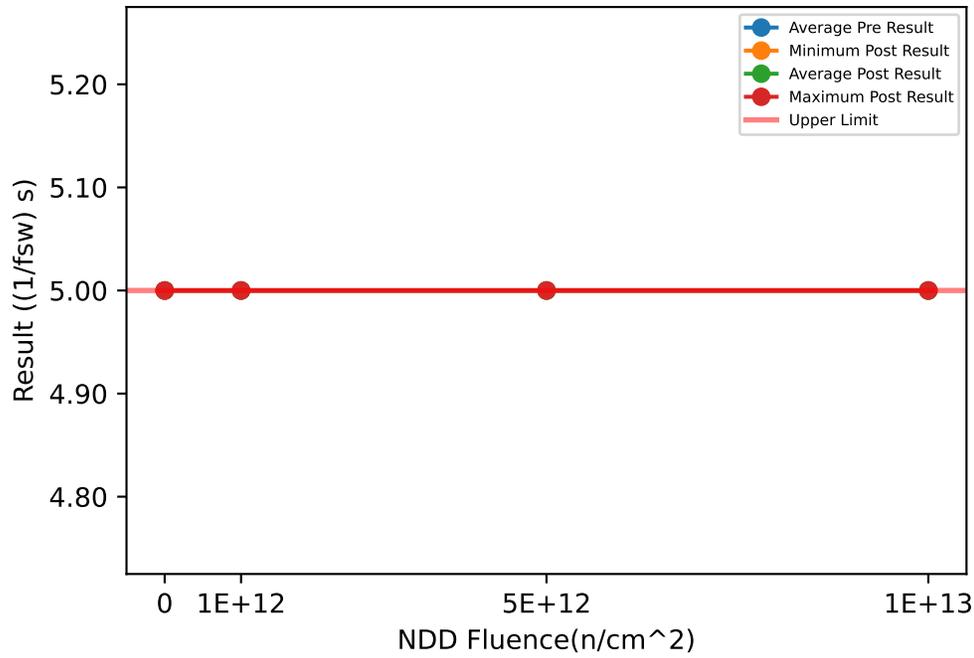| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	5	5	0
2	1e+12	NDD	5	5	0
3	1e+12	NDD	5	5	0
4	1e+12	NDD	5	5	0
5	5e+12	NDD	5	5	0
6	5e+12	NDD	5	5	0
7	5e+12	NDD	5	5	0
8	5e+12	NDD	5	5	0
9	1e+13	NDD	5	5	0
10	1e+13	NDD	5	5	0
11	1e+13	NDD	5	5	0
12	1e+13	NDD	5	5	0
91	0	CORRELATION	5	5	0
92	0	CORRELATION	5	5	0
93	0	CORRELATION	5	5	0
94	0	CORRELATION	5	5	0

Test Statistics ((1/fsw) s)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5	5	5	0	5	5	5	0	0	0	0	0
1e+12	5	5	5	0	5	5	5	0	0	0	0	0
5e+12	5	5	5	0	5	5	5	0	0	0	0	0
1e+13	5	5	5	0	5	5	5	0	0	0	0	0

Device Test: 20.78 FREQ|DETECTION/SYNC/14/14/0/0/5/200kHz//@T_SYNC_DET

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 5.0 ((1/fsw) s))

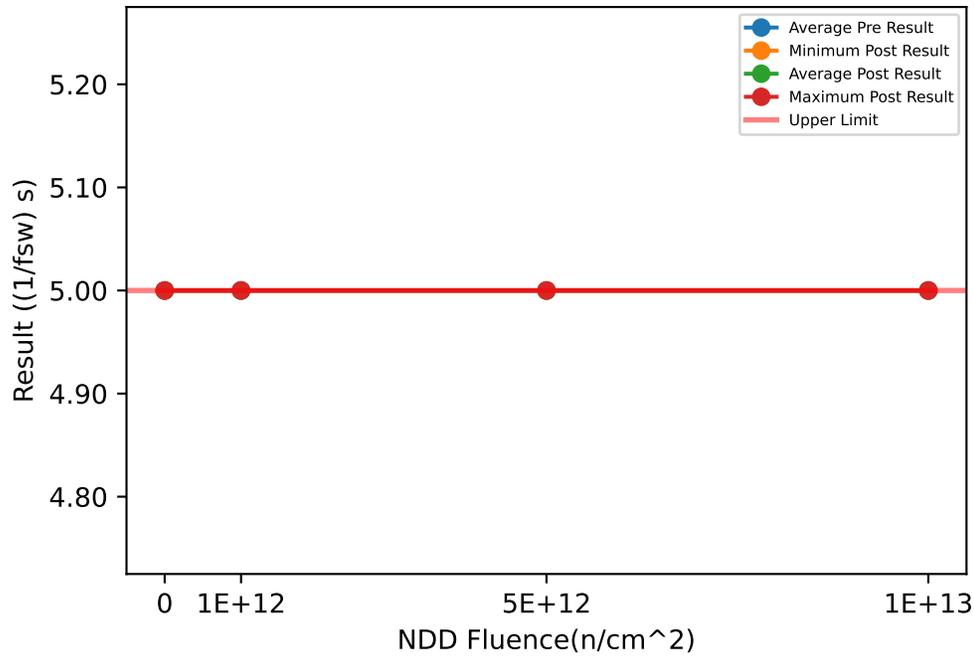| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	5	5	0
2	1e+12	NDD	5	5	0
3	1e+12	NDD	5	5	0
4	1e+12	NDD	5	5	0
5	5e+12	NDD	5	5	0
6	5e+12	NDD	5	5	0
7	5e+12	NDD	5	5	0
8	5e+12	NDD	5	5	0
9	1e+13	NDD	5	5	0
10	1e+13	NDD	5	5	0
11	1e+13	NDD	5	5	0
12	1e+13	NDD	5	5	0
91	0	CORRELATION	5	5	0
92	0	CORRELATION	5	5	0
93	0	CORRELATION	5	5	0
94	0	CORRELATION	5	5	0

Test Statistics ((1/fsw) s)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5	5	5	0	5	5	5	0	0	0	0	0
1e+12	5	5	5	0	5	5	5	0	0	0	0	0
5e+12	5	5	5	0	5	5	5	0	0	0	0	0
1e+13	5	5	5	0	5	5	5	0	0	0	0	0

Device Test: 20.80 FREQ|DETECTION/SYNC/12/12/0/0/5/500kHz//@T_SYNC_DET

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 5.0 ((1/fsw) s))

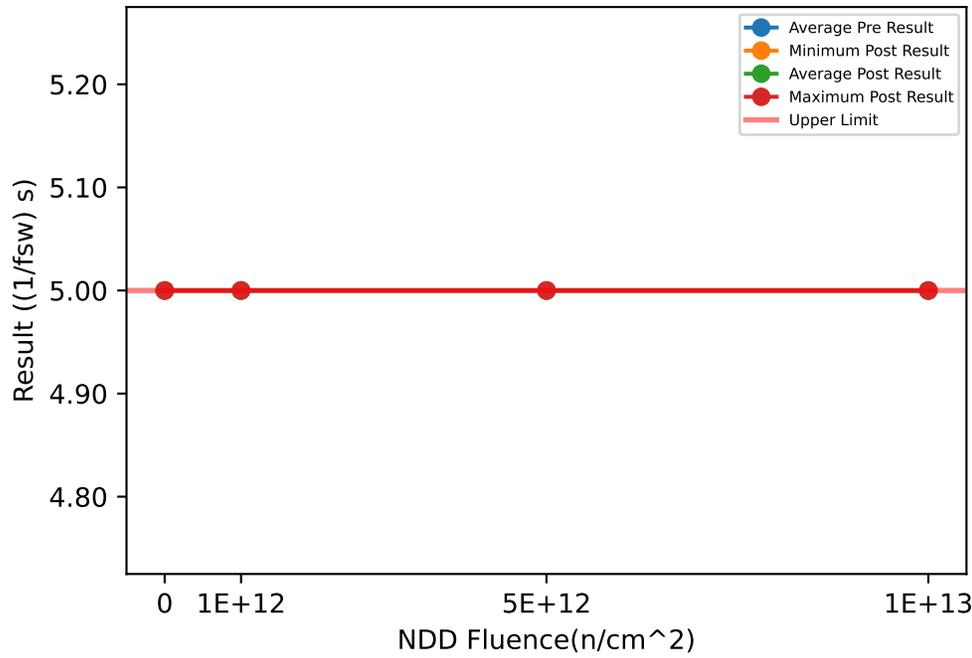| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	5	5	0
2	1e+12	NDD	5	5	0
3	1e+12	NDD	5	5	0
4	1e+12	NDD	5	5	0
5	5e+12	NDD	5	5	0
6	5e+12	NDD	5	5	0
7	5e+12	NDD	5	5	0
8	5e+12	NDD	5	5	0
9	1e+13	NDD	5	5	0
10	1e+13	NDD	5	5	0
11	1e+13	NDD	5	5	0
12	1e+13	NDD	5	5	0
91	0	CORRELATION	5	5	0
92	0	CORRELATION	5	5	0
93	0	CORRELATION	5	5	0
94	0	CORRELATION	5	5	0

Test Statistics ((1/fsw) s)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5	5	5	0	5	5	5	0	0	0	0	0
1e+12	5	5	5	0	5	5	5	0	0	0	0	0
5e+12	5	5	5	0	5	5	5	0	0	0	0	0
1e+13	5	5	5	0	5	5	5	0	0	0	0	0

Device Test: 20.82 FREQ|DETECTION/SYNC/14/14/0/0/5/500kHz//@T_SYNC_DET

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 5.0 ((1/fsw) s))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	5	5	0
2	1e+12	NDD	5	5	0
3	1e+12	NDD	5	5	0
4	1e+12	NDD	5	5	0
5	5e+12	NDD	5	5	0
6	5e+12	NDD	5	5	0
7	5e+12	NDD	5	5	0
8	5e+12	NDD	5	5	0
9	1e+13	NDD	5	5	0
10	1e+13	NDD	5	5	0
11	1e+13	NDD	5	5	0
12	1e+13	NDD	5	5	0
91	0	CORRELATION	5	5	0
92	0	CORRELATION	5	5	0
93	0	CORRELATION	5	5	0
94	0	CORRELATION	5	5	0

Test Statistics ((1/fsw) s)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5	5	5	0	5	5	5	0	0	0	0	0
1e+12	5	5	5	0	5	5	5	0	0	0	0	0
5e+12	5	5	5	0	5	5	5	0	0	0	0	0
1e+13	5	5	5	0	5	5	5	0	0	0	0	0

Device Test: 20.84 FREQ|DETECTION/RT/12/12/0/0/5/100kHz//@T_INT_CLK_DET

NDD vs Result Stats

Legend:
- Average Pre Result
- Minimum Post Result
- Average Post Result
- Maximum Post Result
- Upper Limit

Y-axis: Result ((1/fsw) s); X-axis: NDD Fluence(n/cm^2)

NDD vs Post - Pre Exposure Delta

$R^2 = 0.054$

Y-axis: Delta ((1/fsw) s); X-axis: NDD Fluence(n/cm^2)

Test Results (Upper Limit = 5.0 ((1/fsw) s))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	2.3666	2.3106	-0.056
2	1e+12	NDD	1.8887	2.0301	0.1414
3	1e+12	NDD	2.3639	2.2662	-0.0977
4	1e+12	NDD	1.806	2.0054	0.1994
5	5e+12	NDD	2.4098	2.3391	-0.0707
6	5e+12	NDD	2.0039	1.9096	-0.0943
7	5e+12	NDD	2.4589	2.385	-0.0739
8	5e+12	NDD	1.962	1.9173	-0.0447
9	1e+13	NDD	2.6392	2.2852	-0.354
10	1e+13	NDD	1.9692	2.2324	0.2632
11	1e+13	NDD	2.3057	2.2563	-0.0494
12	1e+13	NDD	1.8892	1.9278	0.0386
91	0	CORRELATION	2.2281	2.4238	0.1957
92	0	CORRELATION	1.9162	2.0215	0.1053
93	0	CORRELATION	2.3835	2.1648	-0.2187
94	0	CORRELATION	1.895	2.0354	0.1404
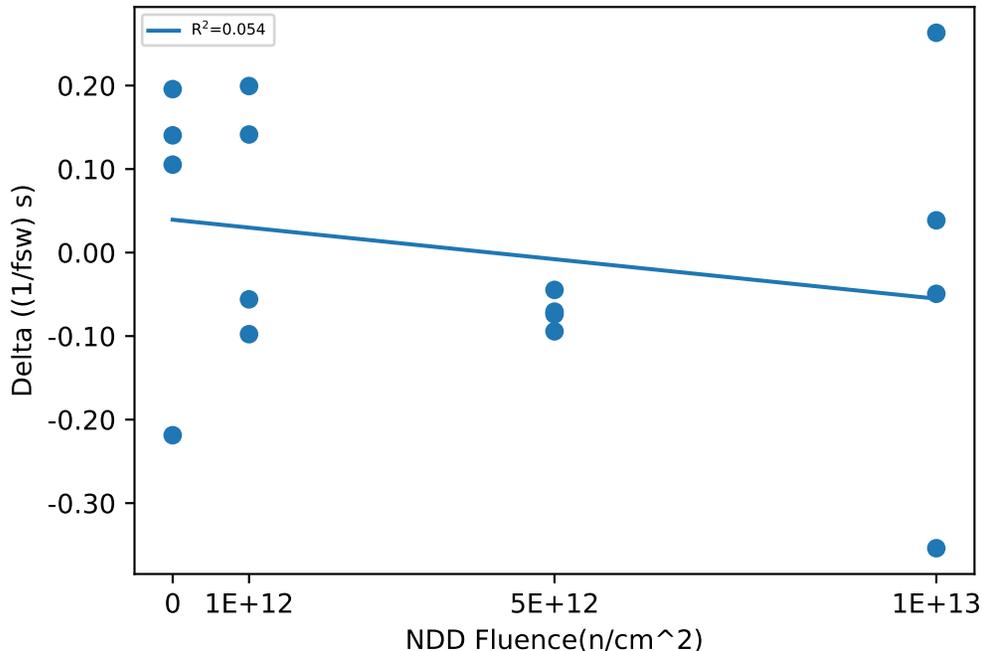
Test Statistics ((1/fsw) s)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.895	2.1057	2.3835	0.23976	2.0215	2.1614	2.4238	0.18647	-0.2187	0.055675	0.1957	0.18666
1e+12	1.806	2.1063	2.3666	0.30091	2.0054	2.1531	2.3106	0.15763	-0.0977	0.046775	0.1994	0.1457
5e+12	1.962	2.2087	2.4589	0.26194	1.9096	2.1378	2.385	0.2597	-0.0943	-0.0709	-0.0447	0.020356
1e+13	1.8892	2.2008	2.6392	0.34348	1.9278	2.1754	2.2852	0.16649	-0.354	-0.0254	0.2632	0.25556
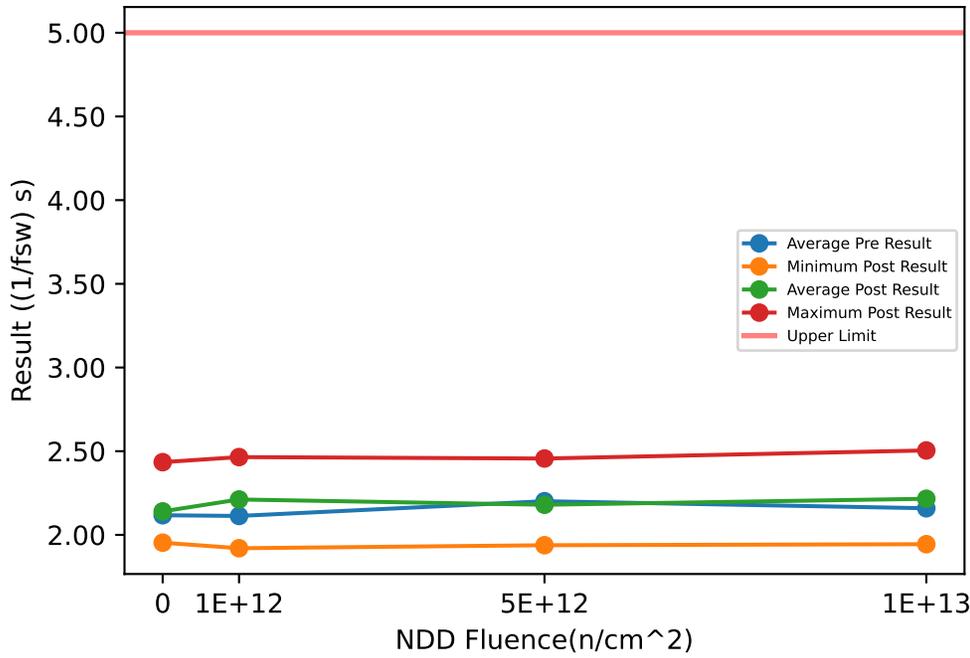
Device Test: 20.86 FREQ|DETECTION/RT/14/14/0/0/5/100kHz//@T_INT_CLK_DET

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 5.0 ((1/fsw) s))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	2.2816	2.4648	0.1832
2	1e+12	NDD	1.859	2.021	0.162
3	1e+12	NDD	2.3329	2.4401	0.1072
4	1e+12	NDD	1.979	1.9203	-0.0587
5	5e+12	NDD	2.4973	2.4562	-0.0411
6	5e+12	NDD	1.8475	1.9382	0.0907
7	5e+12	NDD	2.3645	2.3105	-0.054
8	5e+12	NDD	2.0955	2.0151	-0.0804
9	1e+13	NDD	2.5839	2.5045	-0.0794
10	1e+13	NDD	2.0201	2.1281	0.108
11	1e+13	NDD	2.218	2.2859	0.0679
12	1e+13	NDD	1.8145	1.9444	0.1299
91	0	CORRELATION	2.3016	2.1301	-0.1715
92	0	CORRELATION	1.8831	1.9534	0.0703
93	0	CORRELATION	2.323	2.4344	0.1114
94	0	CORRELATION	1.9619	2.0438	0.0819
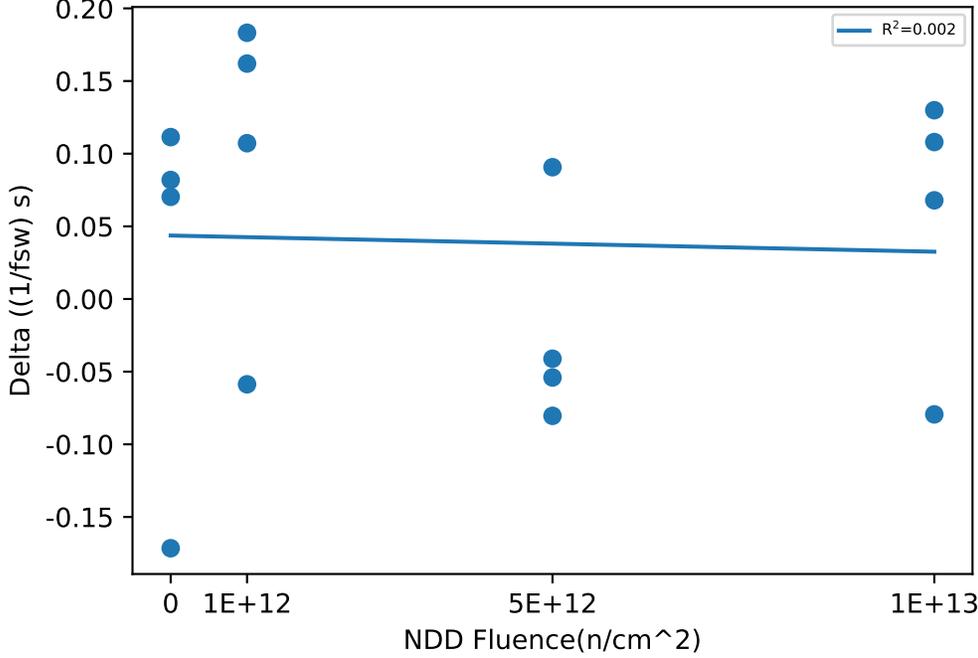
Test Statistics ((1/fsw) s)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.8831	2.1174	2.323	0.22751	1.9534	2.1404	2.4344	0.20884	-0.1715	0.023025	0.1114	0.13083
1e+12	1.859	2.1131	2.3329	0.2304	1.9203	2.2115	2.4648	0.28137	-0.0587	0.098425	0.1832	0.10954
5e+12	1.8475	2.2012	2.4973	0.28903	1.9382	2.18	2.4562	0.24425	-0.0804	-0.0212	0.0907	0.076372
1e+13	1.8145	2.1591	2.5839	0.32761	1.9444	2.2157	2.5045	0.23778	-0.0794	0.0566	0.1299	0.094231
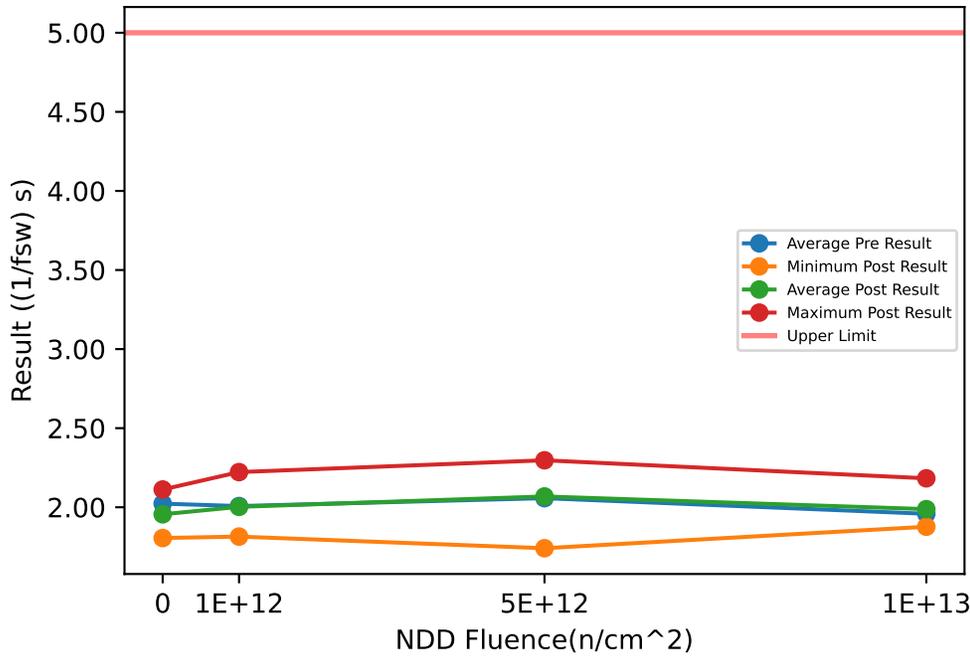
Device Test: 20.88 FREQ|DETECTION/RT/12/12/0/0/5/200kHz//@T_INT_CLK_DET

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 5.0 ((1/fsw) s))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	2.1377	2.2222	0.0845
2	1e+12	NDD	1.8213	1.8878	0.0665
3	1e+12	NDD	2.0618	2.0853	0.0235
4	1e+12	NDD	2.0093	1.8145	-0.1948
5	5e+12	NDD	2.3361	2.2969	-0.0392
6	5e+12	NDD	1.845	2.0047	0.1597
7	5e+12	NDD	2.3083	2.2307	-0.0776
8	5e+12	NDD	1.7401	1.7409	0.0008
9	1e+13	NDD	1.9599	2.0154	0.0555
10	1e+13	NDD	1.8747	1.8767	0.002
11	1e+13	NDD	2.1481	2.1829	0.0348
12	1e+13	NDD	1.852	1.8772	0.0252
91	0	CORRELATION	2.2534	2.0238	-0.2296
92	0	CORRELATION	1.8931	1.8805	-0.0126
93	0	CORRELATION	2.1544	2.1121	-0.0423
94	0	CORRELATION	1.7901	1.8054	0.0153
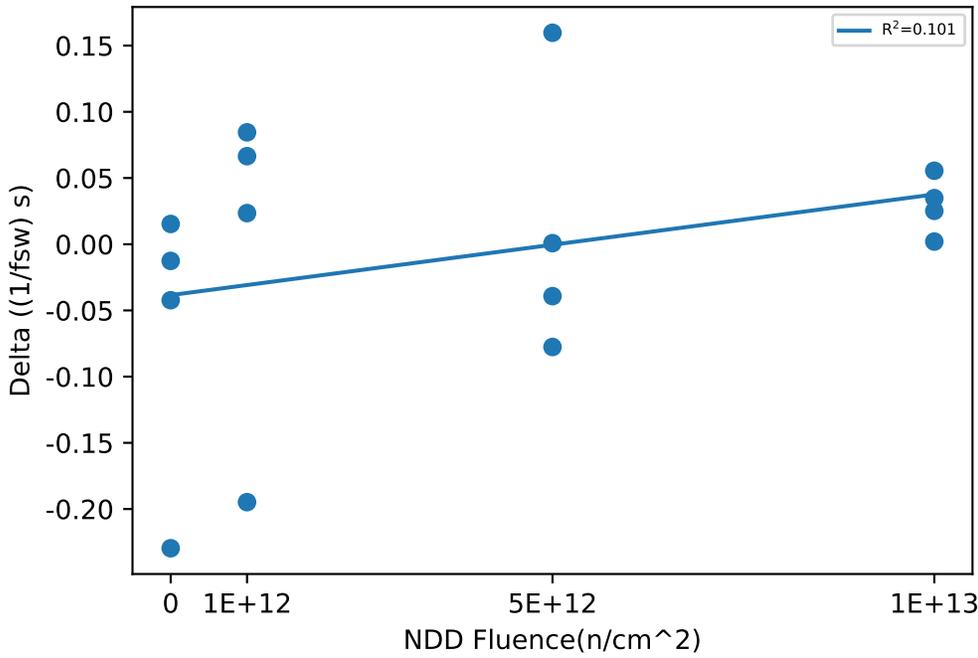
Test Statistics ((1/fsw) s)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.7901	2.0227	2.2534	0.21715	1.8054	1.9554	2.1121	0.13826	-0.2296	-0.0673	0.0153	0.11073
1e+12	1.8213	2.0075	2.1377	0.13488	1.8145	2.0025	2.2222	0.18585	-0.1948	-0.005075	0.0845	0.12905
5e+12	1.7401	2.0574	2.3361	0.30899	1.7409	2.0683	2.2969	0.25157	-0.0776	0.010925	0.1597	0.10422
1e+13	1.852	1.9587	2.1481	0.13455	1.8767	1.9881	2.1829	0.14537	0.002	0.029375	0.0555	0.022202
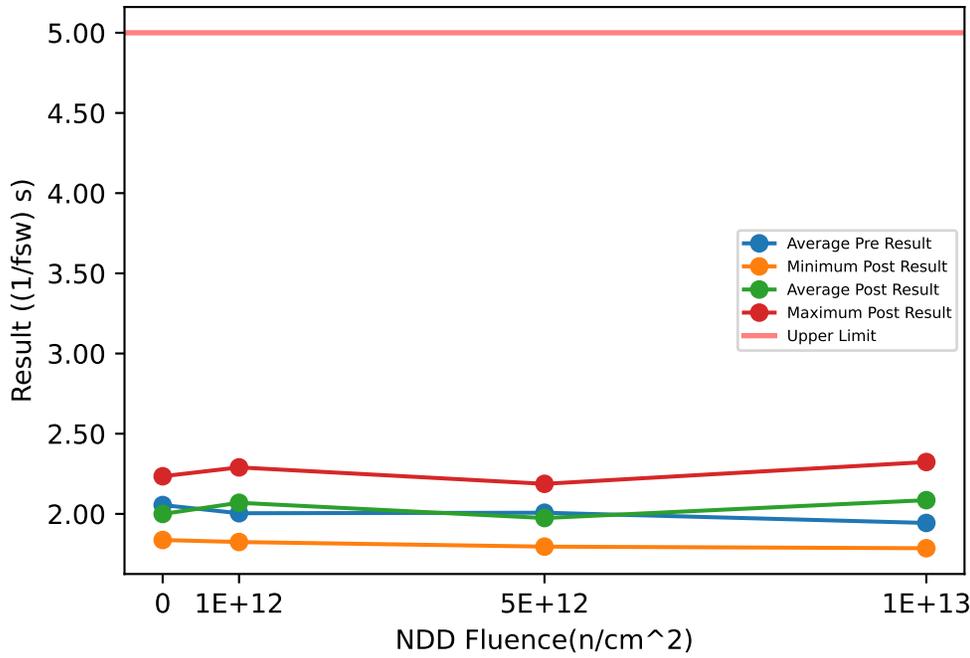
Device Test: 20.90 FREQ|DETECTION/RT/14/14/0/0/5/200kHz//@T_INT_CLK_DET

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 5.0 ((1/fsw) s))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	2.1525	2.2901	0.1376
2	1e+12	NDD	1.8297	2.002	0.1723
3	1e+12	NDD	2.1258	2.1608	0.035
4	1e+12	NDD	1.9087	1.8247	-0.084
5	5e+12	NDD	2.0876	2.1875	0.0999
6	5e+12	NDD	1.9736	1.796	-0.1776
7	5e+12	NDD	2.1967	2.1103	-0.0864
8	5e+12	NDD	1.7715	1.8028	0.0313
9	1e+13	NDD	2.1566	2.3234	0.1668
10	1e+13	NDD	1.8388	1.786	-0.0528
11	1e+13	NDD	2.1668	2.2725	0.1057
12	1e+13	NDD	1.612	1.9607	0.3487
91	0	CORRELATION	2.3497	2.2347	-0.115
92	0	CORRELATION	2.0023	1.9298	-0.0725
93	0	CORRELATION	2.1617	1.9971	-0.1646
94	0	CORRELATION	1.7076	1.8373	0.1297
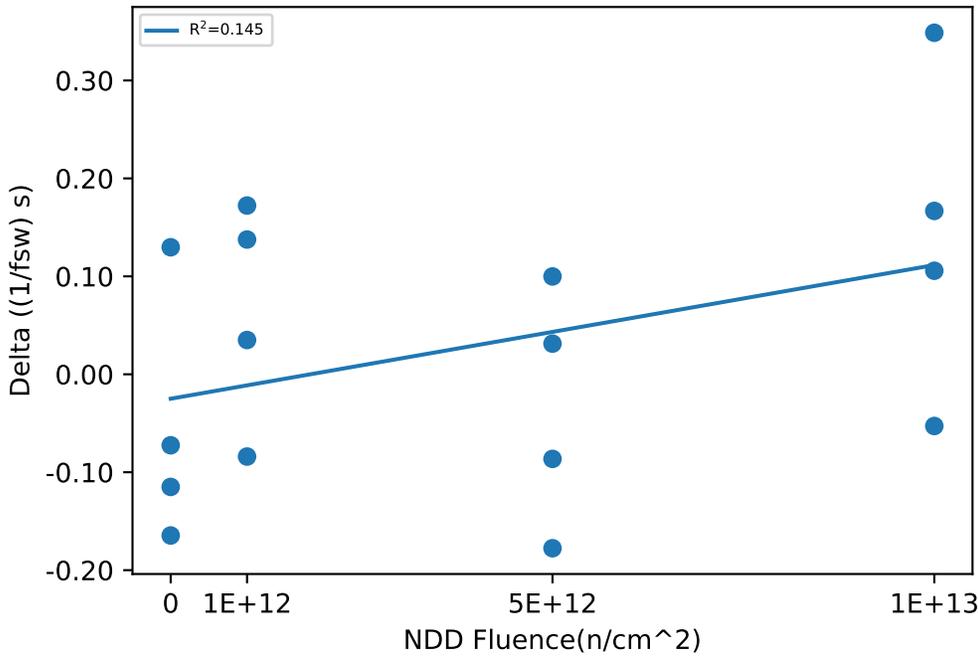
Test Statistics ((1/fsw) s)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.7076	2.0553	2.3497	0.27184	1.8373	1.9997	2.2347	0.1698	-0.1646	-0.0556	0.1297	0.12914
1e+12	1.8297	2.0042	2.1525	0.15953	1.8247	2.0694	2.2901	0.20123	-0.084	0.065225	0.1723	0.1153
5e+12	1.7715	2.0074	2.1967	0.18171	1.796	1.9741	2.1875	0.20425	-0.1776	-0.0332	0.0999	0.12323
1e+13	1.612	1.9436	2.1668	0.26841	1.786	2.0857	2.3234	0.25615	-0.0528	0.1421	0.3487	0.16594
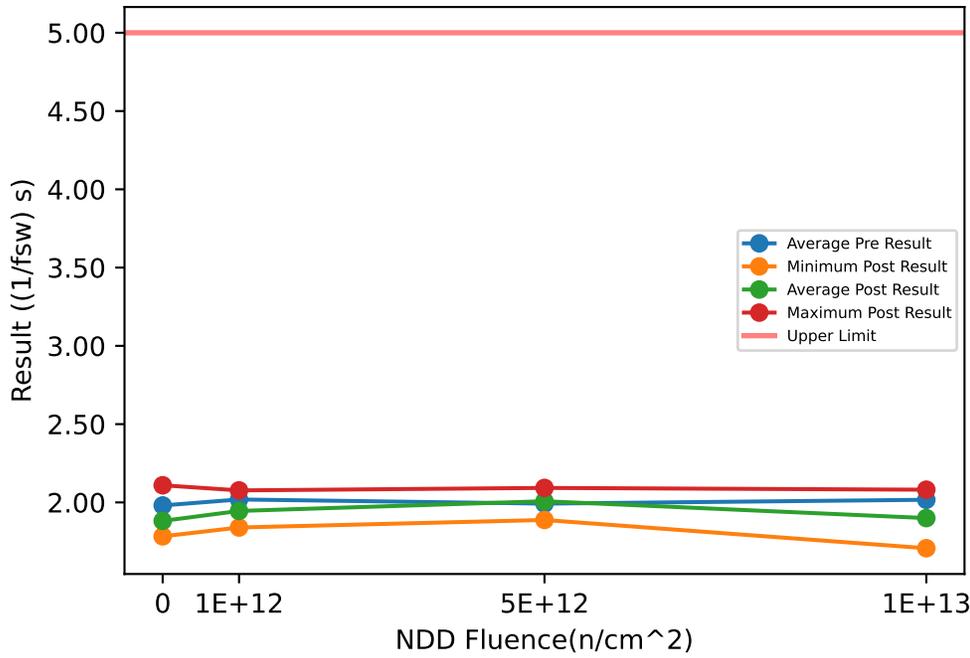
Device Test: 20.92 FREQ|DETECTION/RT/12/12/0/0/5/500kHz//@T_INT_CLK_DET

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 5.0 ((1/fsw) s))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	2.0948	1.9705	-0.1243
2	1e+12	NDD	1.93	1.8947	-0.0353
3	1e+12	NDD	2.1208	2.0767	-0.0441
4	1e+12	NDD	1.9294	1.8397	-0.0897
5	5e+12	NDD	2.0409	2.0646	0.0237
6	5e+12	NDD	2.0004	1.9856	-0.0148
7	5e+12	NDD	2.1545	2.0925	-0.062
8	5e+12	NDD	1.773	1.8878	0.1148
9	1e+13	NDD	2.1455	2.0811	-0.0644
10	1e+13	NDD	1.8728	1.8192	-0.0536
11	1e+13	NDD	2.144	1.992	-0.152
12	1e+13	NDD	1.9048	1.7073	-0.1975
91	0	CORRELATION	1.9672	1.7947	-0.1725
92	0	CORRELATION	1.9256	1.84	-0.0856
93	0	CORRELATION	2.171	2.1094	-0.0616
94	0	CORRELATION	1.8584	1.7832	-0.0752
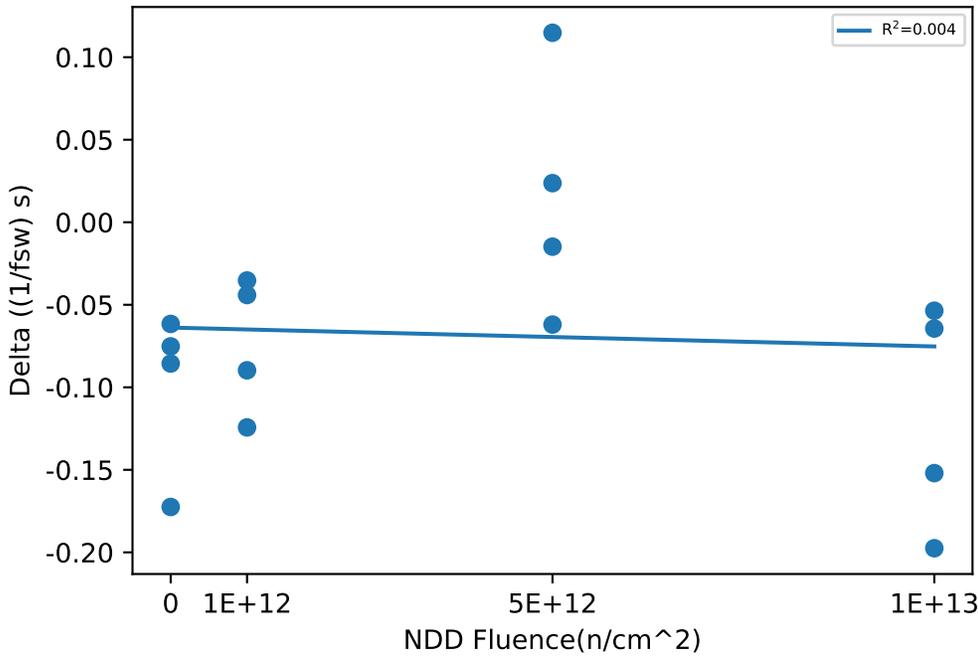
Test Statistics ((1/fsw) s)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.8584	1.9806	2.171	0.13465	1.7832	1.8818	2.1094	0.15369	-0.1725	-0.098725	-0.0616	0.050155
1e+12	1.9294	2.0187	2.1208	0.10337	1.8397	1.9454	2.0767	0.10265	-0.1243	-0.07335	-0.0353	0.041499
5e+12	1.773	1.9922	2.1545	0.16003	1.8878	2.0076	2.0925	0.091821	-0.062	0.015425	0.1148	0.074949
1e+13	1.8728	2.0168	2.1455	0.14835	1.7073	1.8999	2.0811	0.16825	-0.1975	-0.11688	-0.0536	0.069502
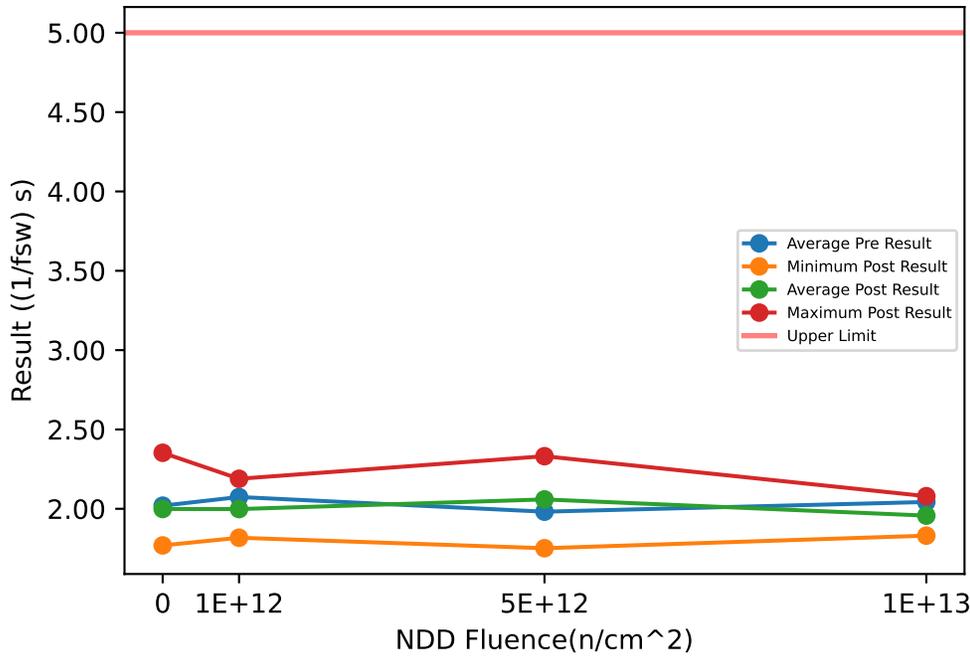
Device Test: 20.94 FREQ|DETECTION/RT/14/14/0/0/5/500kHz//@T_INT_CLK_DET

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 5.0 ((1/fsw) s))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	2.0889	2.1622	0.0733
2	1e+12	NDD	2.0272	1.8176	-0.2096
3	1e+12	NDD	2.2844	2.1891	-0.0953
4	1e+12	NDD	1.8968	1.8239	-0.0729
5	5e+12	NDD	2.0002	2.3315	0.3313
6	5e+12	NDD	1.8214	1.7515	-0.0699
7	5e+12	NDD	2.1917	2.0759	-0.1158
8	5e+12	NDD	1.9139	2.0774	0.1635
9	1e+13	NDD	2.2199	2.0795	-0.1404
10	1e+13	NDD	2.0803	1.8307	-0.2496
11	1e+13	NDD	1.9769	1.9926	0.0157
12	1e+13	NDD	1.8943	1.9251	0.0308
91	0	CORRELATION	2.2521	2.353	0.1009
92	0	CORRELATION	1.823	1.8852	0.0622
93	0	CORRELATION	2.1442	1.9876	-0.1566
94	0	CORRELATION	1.8594	1.7692	-0.0902
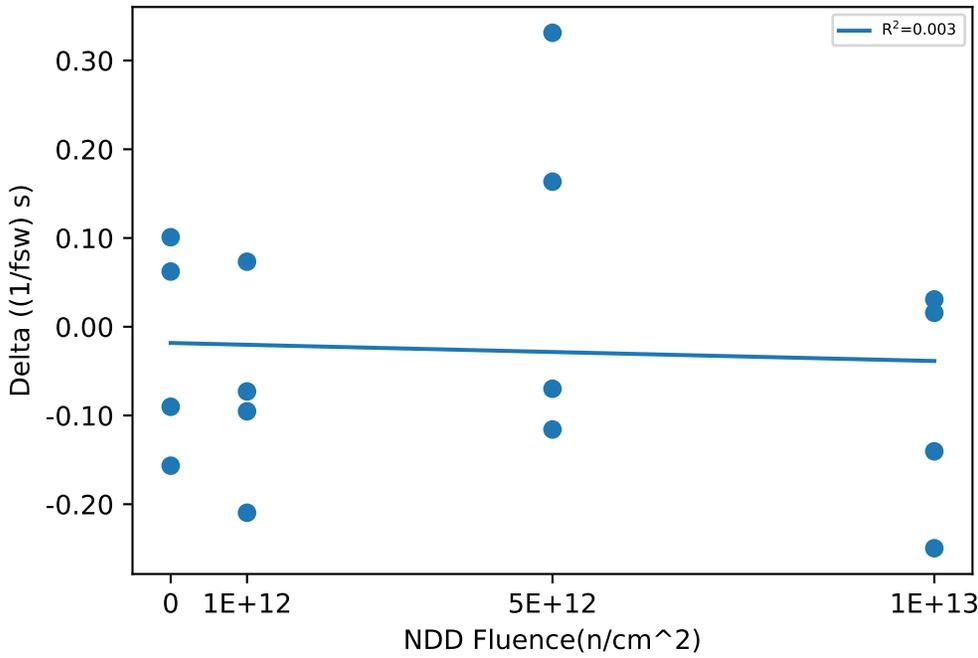
Test Statistics ((1/fsw) s)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.823	2.0197	2.2521	0.21126	1.7692	1.9988	2.353	0.25246	-0.1566	-0.020925	0.1009	0.12242
1e+12	1.8968	2.0743	2.2844	0.16133	1.8176	1.9982	2.1891	0.20521	-0.2096	-0.076125	0.0733	0.11622
5e+12	1.8214	1.9818	2.1917	0.15783	1.7515	2.0591	2.3315	0.23765	-0.1158	0.077275	0.3313	0.20889
1e+13	1.8943	2.0429	2.2199	0.14043	1.8307	1.957	2.0795	0.10527	-0.2496	-0.085875	0.0308	0.1338
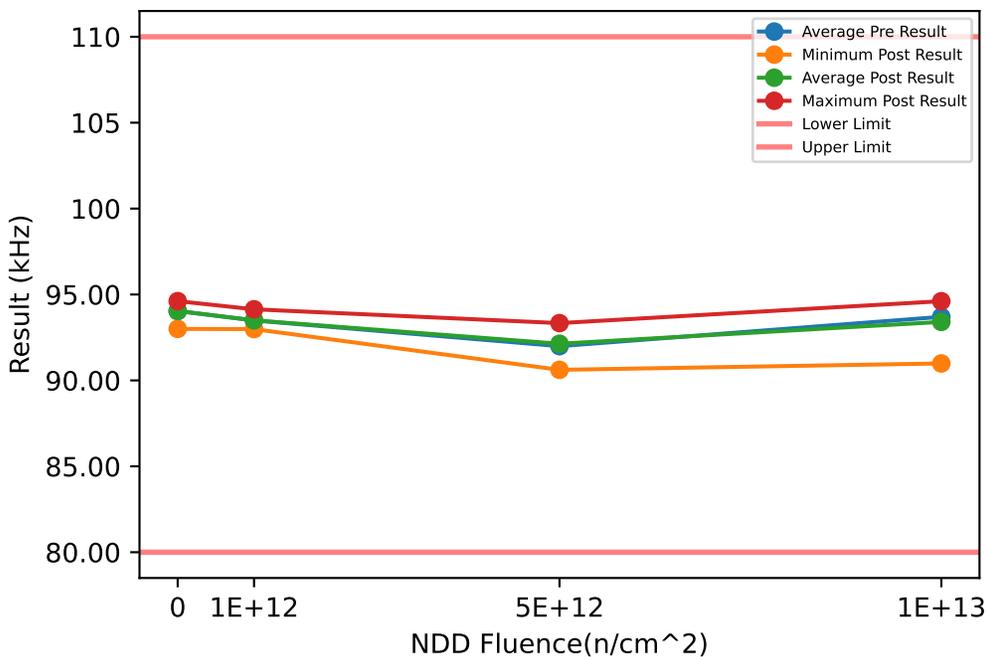
Device Test: 20.97 LEVEL|FREQ/RT/8/8/0/0/5/100kHz//@FSW_EXT_RT_A

## NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 80.0, Upper Limit = 110.0 (kHz))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	92.912	92.986	0.0737
2	1e+12	NDD	94.101	94.138	0.0379
3	1e+12	NDD	93.722	93.631	-0.0903
4	1e+12	NDD	93.229	93.228	-0.0014
5	5e+12	NDD	90.372	90.616	0.2438
6	5e+12	NDD	92.727	92.799	0.0727
7	5e+12	NDD	91.835	91.787	-0.0475
8	5e+12	NDD	93.037	93.334	0.2973
9	1e+13	NDD	91.09	90.987	-0.1024
10	1e+13	NDD	94.547	94.061	-0.4856
11	1e+13	NDD	94.926	94.61	-0.3162
12	1e+13	NDD	94.232	93.962	-0.2704
91	0	CORRELATION	93.987	93.995	0.0088
92	0	CORRELATION	94.532	94.555	0.0228
93	0	CORRELATION	93.028	92.999	-0.029
94	0	CORRELATION	94.604	94.614	0.0093
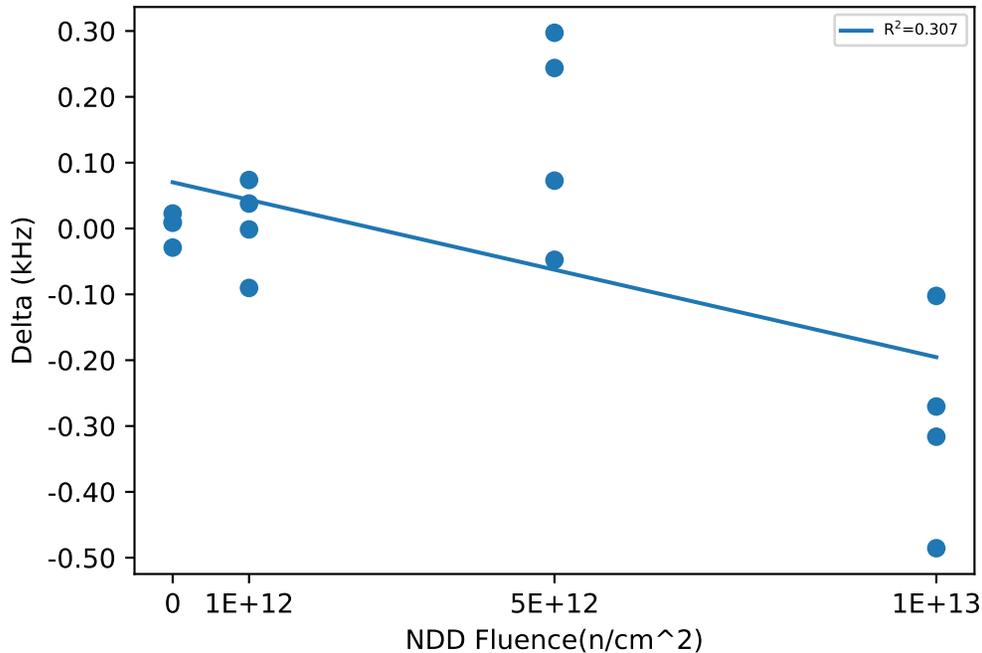
Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	93.028	94.038	94.604	0.72753	92.999	94.041	94.614	0.74836	-0.029	0.002975	0.0228	0.022281
1e+12	92.912	93.491	94.101	0.52543	92.986	93.496	94.138	0.50436	-0.0903	0.004975	0.0737	0.070534
5e+12	90.372	91.992	93.037	1.1945	90.616	92.134	93.334	1.1983	-0.0475	0.14157	0.2973	0.15832
1e+13	91.09	93.699	94.926	1.7625	90.987	93.405	94.61	1.637	-0.4856	-0.29365	-0.1024	0.15755
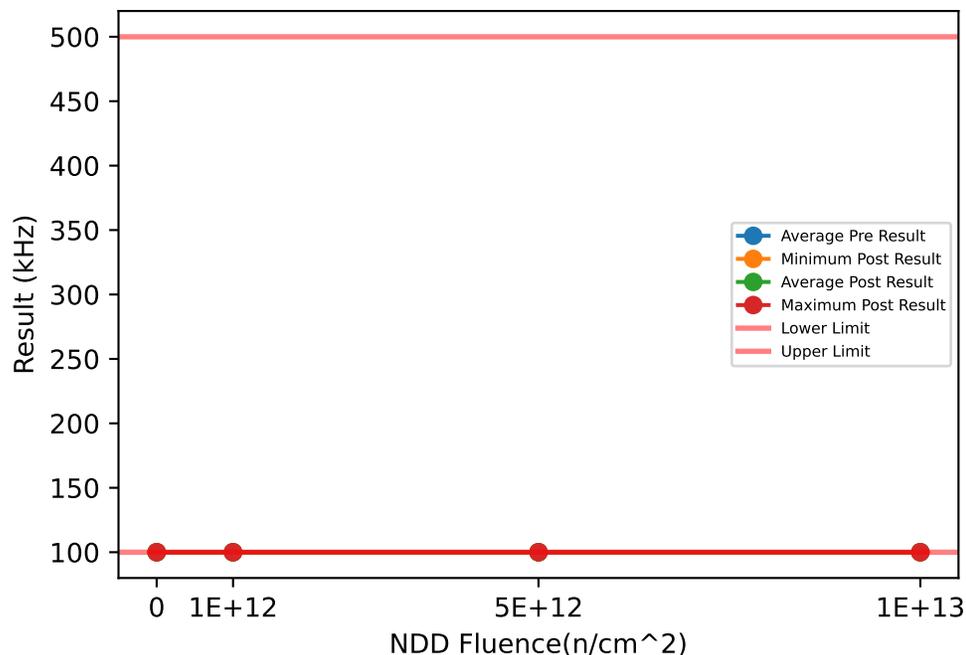
Device Test: 20.98 LEVEL|FREQ/SYNC/8/8/0/0/5/100kHz//@FREQ_SYNC_EXT_503X

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 100.0, Upper Limit = 500.0 (kHz))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	100	99.999	-0.0006
2	1e+12	NDD	99.994	100	0.0077
3	1e+12	NDD	99.994	99.999	0.0051
4	1e+12	NDD	99.994	100	0.0075
5	5e+12	NDD	99.996	99.999	0.0031
6	5e+12	NDD	99.994	100	0.0075
7	5e+12	NDD	99.992	100	0.0094
8	5e+12	NDD	99.994	100	0.0078
9	1e+13	NDD	99.996	99.999	0.0034
10	1e+13	NDD	99.995	100	0.0053
11	1e+13	NDD	99.992	99.999	0.0074
12	1e+13	NDD	99.994	99.999	0.0055
91	0	CORRELATION	99.995	99.998	0.003
92	0	CORRELATION	99.994	100	0.0056
93	0	CORRELATION	99.993	100	0.0078
94	0	CORRELATION	99.994	100	0.007
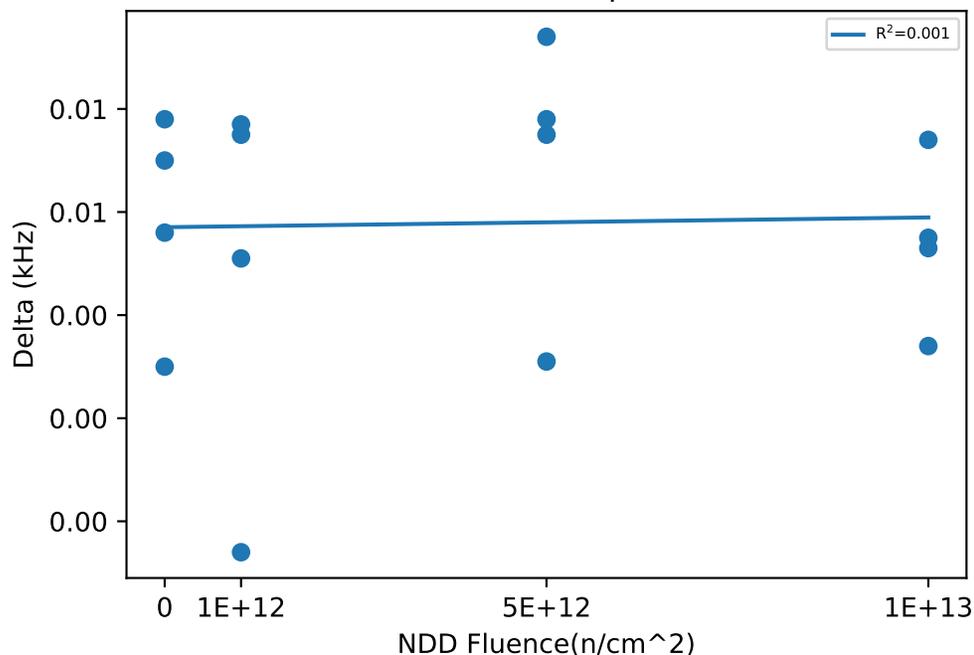
Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	99.993	99.994	99.995	0.00080416	99.998	100	100	0.0013675	0.003	0.00585	0.0078	0.0021063
1e+12	99.994	99.995	100	0.0030192	99.999	100	100	0.0012832	-0.0006	0.004925	0.0077	0.0038681
5e+12	99.992	99.994	99.996	0.001885	99.999	100	100	0.0010661	0.0031	0.00695	0.0094	0.0026988
1e+13	99.992	99.994	99.996	0.0017292	99.999	100	100	0.00036968	0.0034	0.0054	0.0074	0.001635

Device Test: 20.99 PF|DCL_40/SYNC/8/8/0/0/5/100kHz//@DUTY_SYNC_EXT

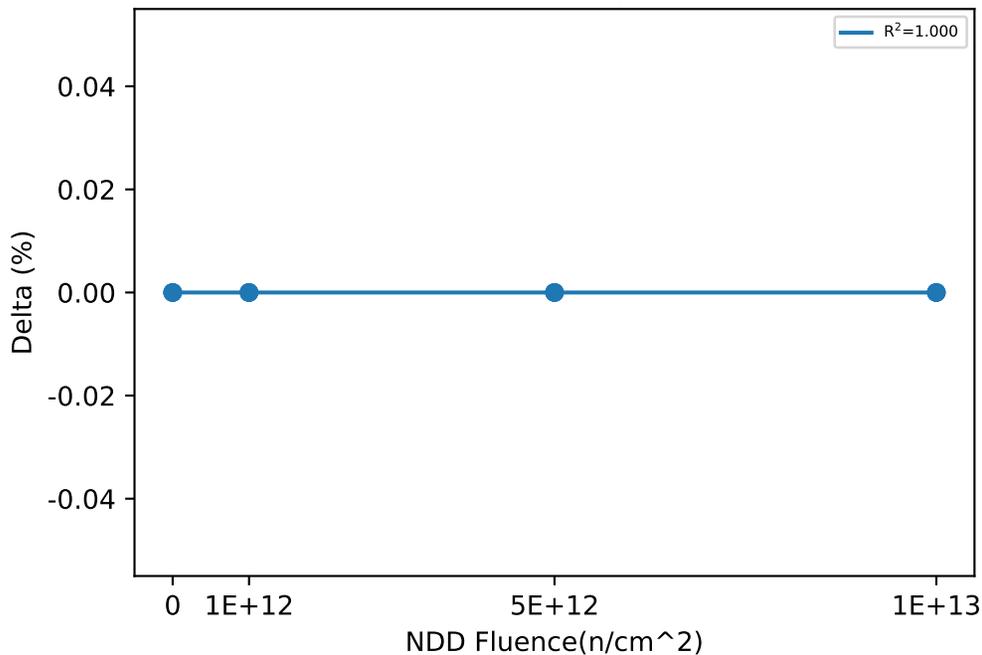## NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 40.0, Upper Limit = 60.0 (%))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	40	40	0
2	1e+12	NDD	40	40	0
3	1e+12	NDD	40	40	0
4	1e+12	NDD	40	40	0
5	5e+12	NDD	40	40	0
6	5e+12	NDD	40	40	0
7	5e+12	NDD	40	40	0
8	5e+12	NDD	40	40	0
9	1e+13	NDD	40	40	0
10	1e+13	NDD	40	40	0
11	1e+13	NDD	40	40	0
12	1e+13	NDD	40	40	0
91	0	CORRELATION	40	40	0
92	0	CORRELATION	40	40	0
93	0	CORRELATION	40	40	0
94	0	CORRELATION	40	40	0

Test Statistics (%)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	40	40	40	0	40	40	40	0	0	0	0	0
1e+12	40	40	40	0	40	40	40	0	0	0	0	0
5e+12	40	40	40	0	40	40	40	0	0	0	0	0
1e+13	40	40	40	0	40	40	40	0	0	0	0	0

Device Test: 21.11 VOLTAGE|VREF/VREF/14/14/0/0/5/500kHz//@V_REFCAP

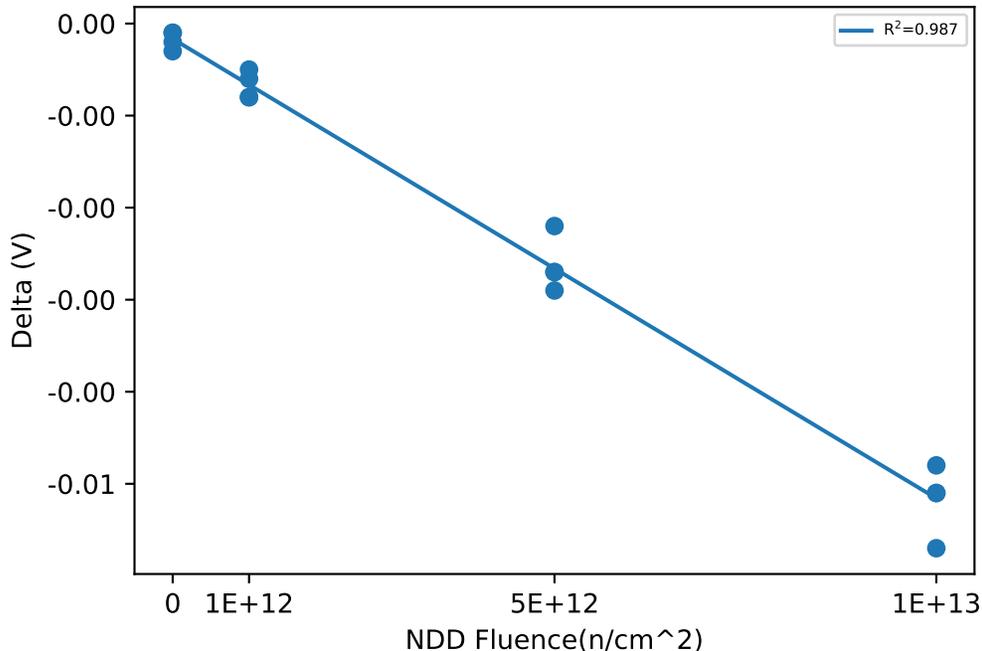## NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.2235	1.2229	-0.0006
2	1e+12	NDD	1.2236	1.2228	-0.0008
3	1e+12	NDD	1.2219	1.2214	-0.0005
4	1e+12	NDD	1.2245	1.2237	-0.0008
5	5e+12	NDD	1.2217	1.219	-0.0027
6	5e+12	NDD	1.2229	1.22	-0.0029
7	5e+12	NDD	1.2208	1.2186	-0.0022
8	5e+12	NDD	1.2227	1.22	-0.0027
9	1e+13	NDD	1.2217	1.2166	-0.0051
10	1e+13	NDD	1.2227	1.217	-0.0057
11	1e+13	NDD	1.22	1.2152	-0.0048
12	1e+13	NDD	1.2211	1.216	-0.0051
91	0	CORRELATION	1.2205	1.2204	-0.0001
92	0	CORRELATION	1.2234	1.2232	-0.0002
93	0	CORRELATION	1.2235	1.2234	-0.0001
94	0	CORRELATION	1.2223	1.222	-0.0003

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2205	1.2224	1.2235	0.0013937	1.2204	1.2223	1.2234	0.0013796	-0.0003	-0.000175	-0.0001	9.5743e-05
1e+12	1.2219	1.2234	1.2245	0.0010813	1.2214	1.2227	1.2237	0.00095568	-0.0008	-0.000675	-0.0005	0.00015
5e+12	1.2208	1.222	1.2229	0.00097082	1.2186	1.2194	1.22	0.00071181	-0.0029	-0.002625	-0.0022	0.00029861
1e+13	1.22	1.2214	1.2227	0.0011295	1.2152	1.2162	1.217	0.00078316	-0.0057	-0.005175	-0.0048	0.00037749
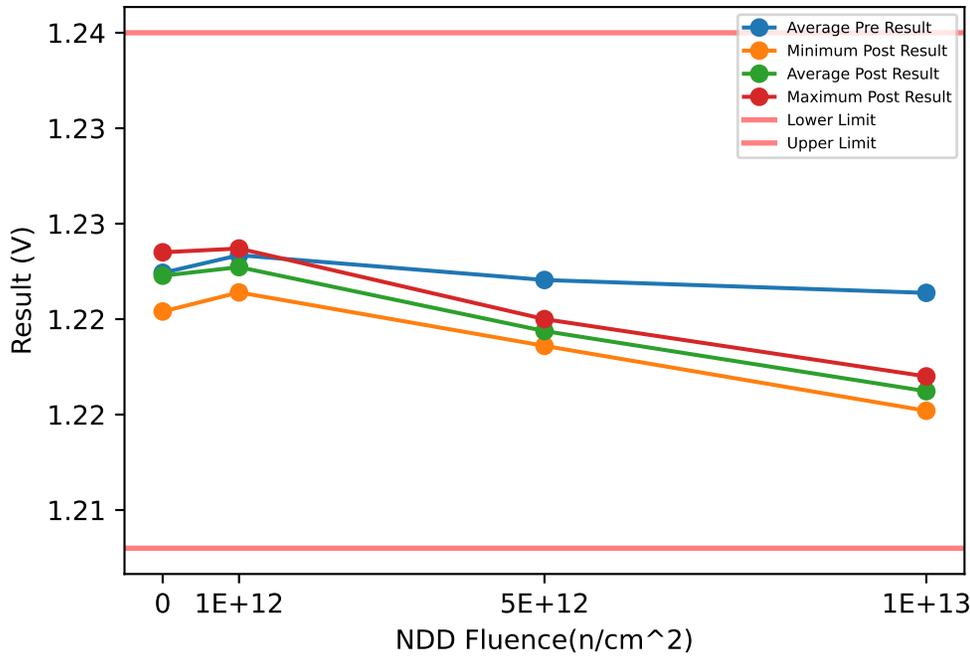
Device Test: 21.13 VOLTAGE|VREF/VREF/12/12/0/1000/5/100kHz//@V_REFCAP

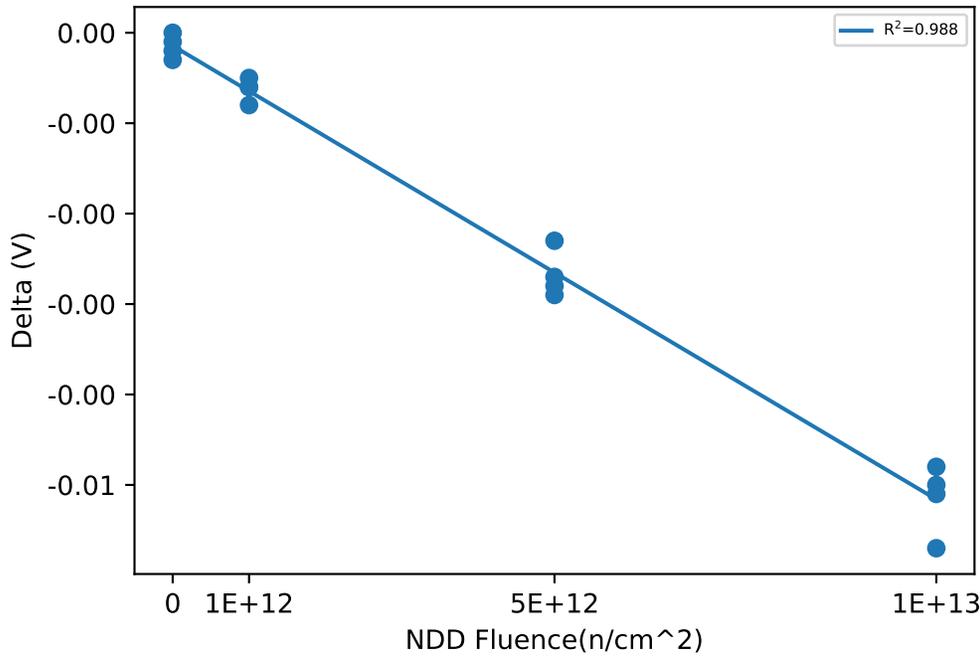NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.2235	1.2229	-0.0006
2	1e+12	NDD	1.2235	1.2229	-0.0006
3	1e+12	NDD	1.2219	1.2214	-0.0005
4	1e+12	NDD	1.2245	1.2237	-0.0008
5	5e+12	NDD	1.2217	1.219	-0.0027
6	5e+12	NDD	1.2229	1.22	-0.0029
7	5e+12	NDD	1.2209	1.2186	-0.0023
8	5e+12	NDD	1.2227	1.2199	-0.0028
9	1e+13	NDD	1.2217	1.2167	-0.005
10	1e+13	NDD	1.2227	1.217	-0.0057
11	1e+13	NDD	1.22	1.2152	-0.0048
12	1e+13	NDD	1.2211	1.216	-0.0051
91	0	CORRELATION	1.2205	1.2204	-0.0001
92	0	CORRELATION	1.2234	1.2232	-0.0002
93	0	CORRELATION	1.2235	1.2235	0
94	0	CORRELATION	1.2223	1.222	-0.0003

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2205	1.2224	1.2235	0.0013937	1.2204	1.2223	1.2235	0.001408	-0.0003	-0.00015	0	0.0001291
1e+12	1.2219	1.2233	1.2245	0.0010755	1.2214	1.2227	1.2237	0.00096047	-0.0008	-0.000625	-0.0005	0.00012583
5e+12	1.2209	1.2221	1.2229	0.00092916	1.2186	1.2194	1.22	0.00068496	-0.0029	-0.002675	-0.0023	0.000263
1e+13	1.22	1.2214	1.2227	0.0011295	1.2152	1.2162	1.217	0.00080156	-0.0057	-0.00515	-0.0048	0.0003873
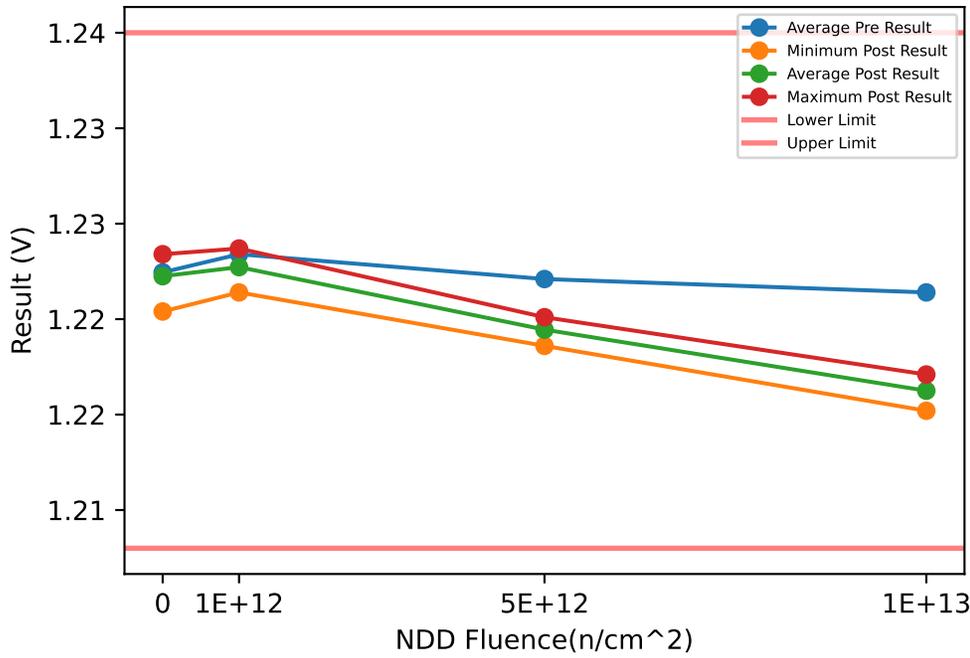
Device Test: 21.15 VOLTAGE|VREF/VREF/14/14/0/1000/5/100kHz//@V_REFCAP

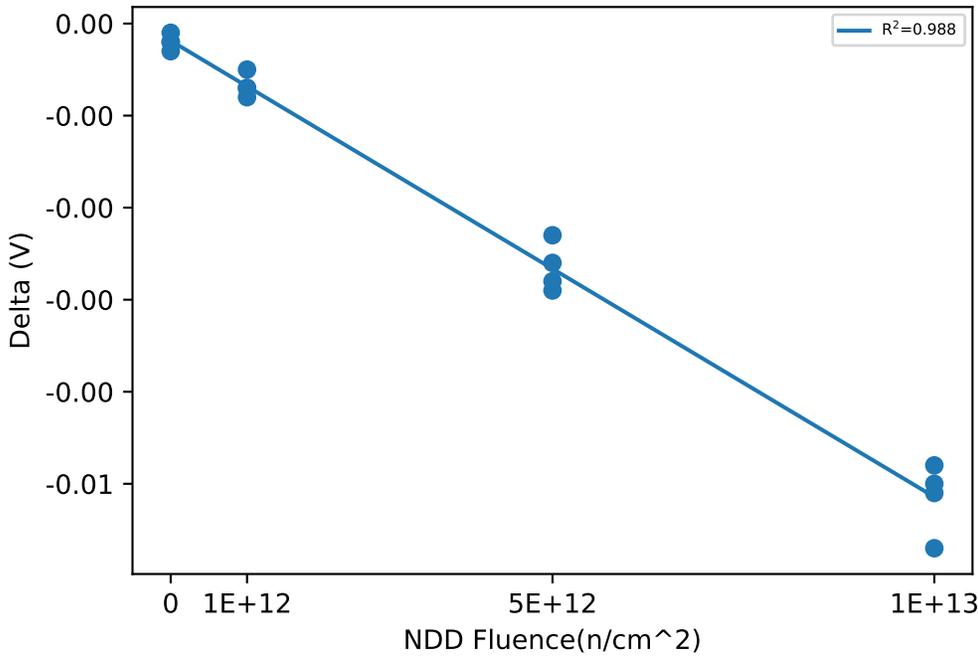

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.2236	1.2229	-0.0007
2	1e+12	NDD	1.2236	1.2229	-0.0007
3	1e+12	NDD	1.2219	1.2214	-0.0005
4	1e+12	NDD	1.2245	1.2237	-0.0008
5	5e+12	NDD	1.2217	1.2191	-0.0026
6	5e+12	NDD	1.223	1.2201	-0.0029
7	5e+12	NDD	1.2209	1.2186	-0.0023
8	5e+12	NDD	1.2228	1.22	-0.0028
9	1e+13	NDD	1.2217	1.2167	-0.005
10	1e+13	NDD	1.2228	1.2171	-0.0057
11	1e+13	NDD	1.22	1.2152	-0.0048
12	1e+13	NDD	1.2211	1.216	-0.0051
91	0	CORRELATION	1.2206	1.2204	-0.0002
92	0	CORRELATION	1.2234	1.2232	-0.0002
93	0	CORRELATION	1.2235	1.2234	-0.0001
94	0	CORRELATION	1.2223	1.222	-0.0003

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2206	1.2225	1.2235	0.0013478	1.2204	1.2223	1.2234	0.0013796	-0.0003	-0.0002	-0.0001	8.165e-05
1e+12	1.2219	1.2234	1.2245	0.0010863	1.2214	1.2227	1.2237	0.00096047	-0.0008	-0.000675	-0.0005	0.00012583
5e+12	1.2209	1.2221	1.223	0.00098319	1.2186	1.2194	1.2201	0.00072342	-0.0029	-0.00265	-0.0023	0.00026458
1e+13	1.22	1.2214	1.2228	0.001169	1.2152	1.2163	1.2171	0.00083467	-0.0057	-0.00515	-0.0048	0.0003873

Device Test: 21.17 VOLTAGE|VREF/VREF/12/12/0/1000/5/500kHz//@V_REFCAP

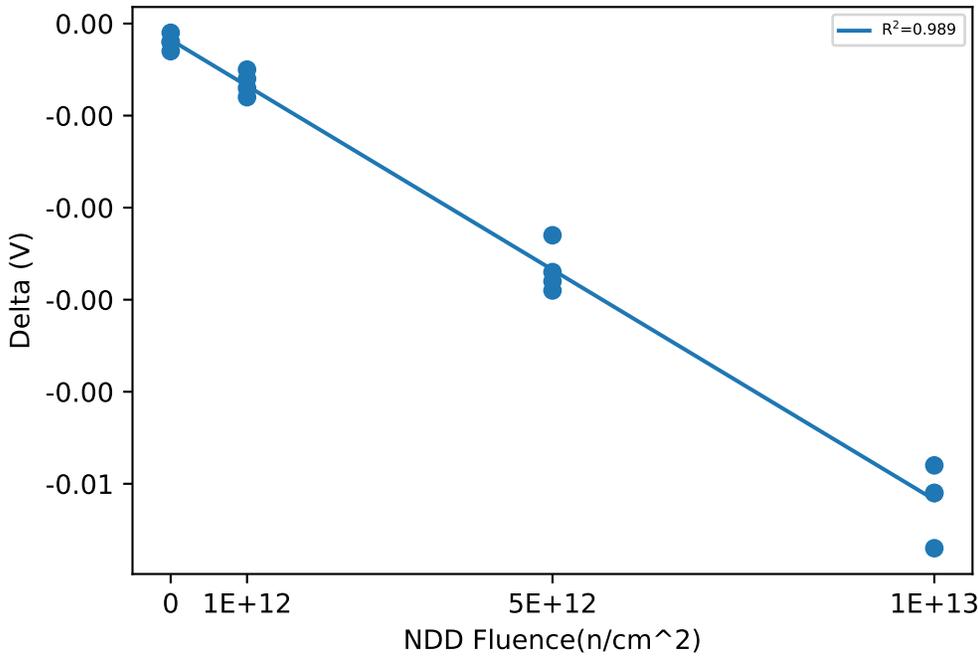## NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.2234	1.2228	-0.0006
2	1e+12	NDD	1.2235	1.2228	-0.0007
3	1e+12	NDD	1.2218	1.2213	-0.0005
4	1e+12	NDD	1.2244	1.2236	-0.0008
5	5e+12	NDD	1.2216	1.2189	-0.0027
6	5e+12	NDD	1.2229	1.22	-0.0029
7	5e+12	NDD	1.2208	1.2185	-0.0023
8	5e+12	NDD	1.2227	1.2199	-0.0028
9	1e+13	NDD	1.2217	1.2166	-0.0051
10	1e+13	NDD	1.2227	1.217	-0.0057
11	1e+13	NDD	1.2199	1.2151	-0.0048
12	1e+13	NDD	1.221	1.2159	-0.0051
91	0	CORRELATION	1.2205	1.2203	-0.0002
92	0	CORRELATION	1.2233	1.2231	-0.0002
93	0	CORRELATION	1.2234	1.2233	-0.0001
94	0	CORRELATION	1.2222	1.2219	-0.0003

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2205	1.2224	1.2234	0.0013478	1.2203	1.2222	1.2233	0.0013796	-0.0003	-0.0002	-0.0001	8.165e-05
1e+12	1.2218	1.2233	1.2244	0.0010813	1.2213	1.2226	1.2236	0.00096047	-0.0008	-0.00065	-0.0005	0.0001291
5e+12	1.2208	1.222	1.2229	0.00098319	1.2185	1.2193	1.22	0.00074106	-0.0029	-0.002675	-0.0023	0.000263
1e+13	1.2199	1.2213	1.2227	0.0011786	1.2151	1.2162	1.217	0.00083467	-0.0057	-0.005175	-0.0048	0.00037749

Device Test: 21.19 VOLTAGE|VREF/VREF/14/14/0/1000/5/500kHz//@V_REFCAP

NDD vs Result Stats

Legend: Average Pre Result, Minimum Post Result, Average Post Result, Maximum Post Result, Lower Limit, Upper Limit

NDD vs Post - Pre Exposure Delta

R²=0.989

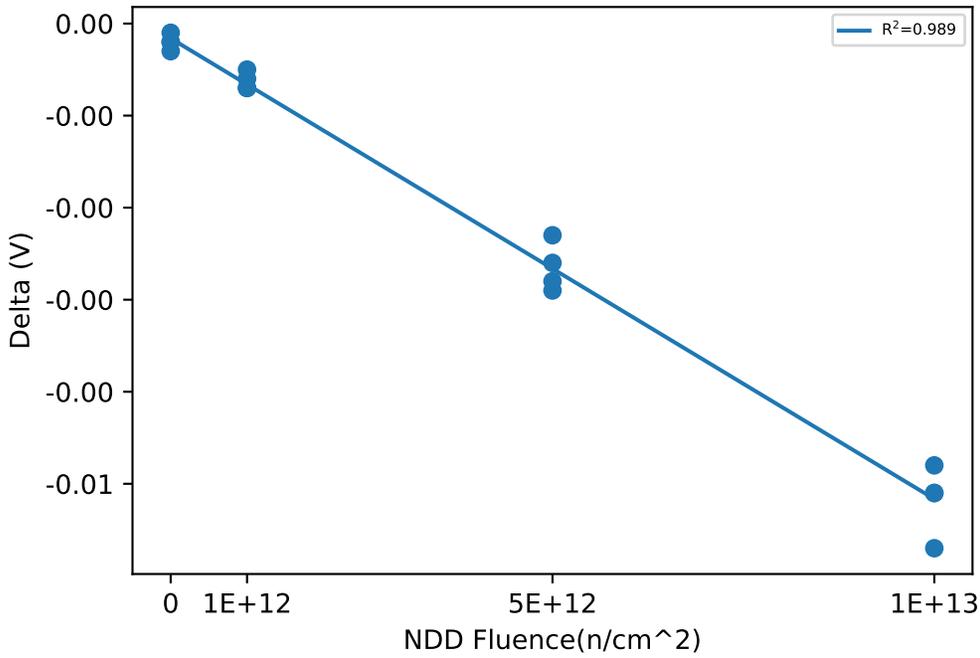## Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.2234	1.2228	-0.0006
2	1e+12	NDD	1.2235	1.2228	-0.0007
3	1e+12	NDD	1.2218	1.2213	-0.0005
4	1e+12	NDD	1.2244	1.2237	-0.0007
5	5e+12	NDD	1.2216	1.219	-0.0026
6	5e+12	NDD	1.2229	1.22	-0.0029
7	5e+12	NDD	1.2208	1.2185	-0.0023
8	5e+12	NDD	1.2227	1.2199	-0.0028
9	1e+13	NDD	1.2217	1.2166	-0.0051
10	1e+13	NDD	1.2227	1.217	-0.0057
11	1e+13	NDD	1.2199	1.2151	-0.0048
12	1e+13	NDD	1.221	1.2159	-0.0051
91	0	CORRELATION	1.2205	1.2203	-0.0002
92	0	CORRELATION	1.2234	1.2232	-0.0002
93	0	CORRELATION	1.2234	1.2233	-0.0001
94	0	CORRELATION	1.2222	1.2219	-0.0003

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2205	1.2224	1.2234	0.001372	1.2203	1.2222	1.2233	0.0014033	-0.0003	-0.0002	-0.0001	8.165e-05
1e+12	1.2218	1.2233	1.2244	0.0010813	1.2213	1.2227	1.2237	0.00099499	-0.0007	-0.000625	-0.0005	9.5743e-05
5e+12	1.2208	1.222	1.2229	0.00098319	1.2185	1.2193	1.22	0.00072342	-0.0029	-0.00265	-0.0023	0.00026458
1e+13	1.2199	1.2213	1.2227	0.0011786	1.2151	1.2162	1.217	0.00083467	-0.0057	-0.005175	-0.0048	0.00037749

Device Test: 21.23 VOLTAGE|VREF/VREF/8/8/0/0/5/100kHz//@V_REFCAP

NDD vs Result Stats
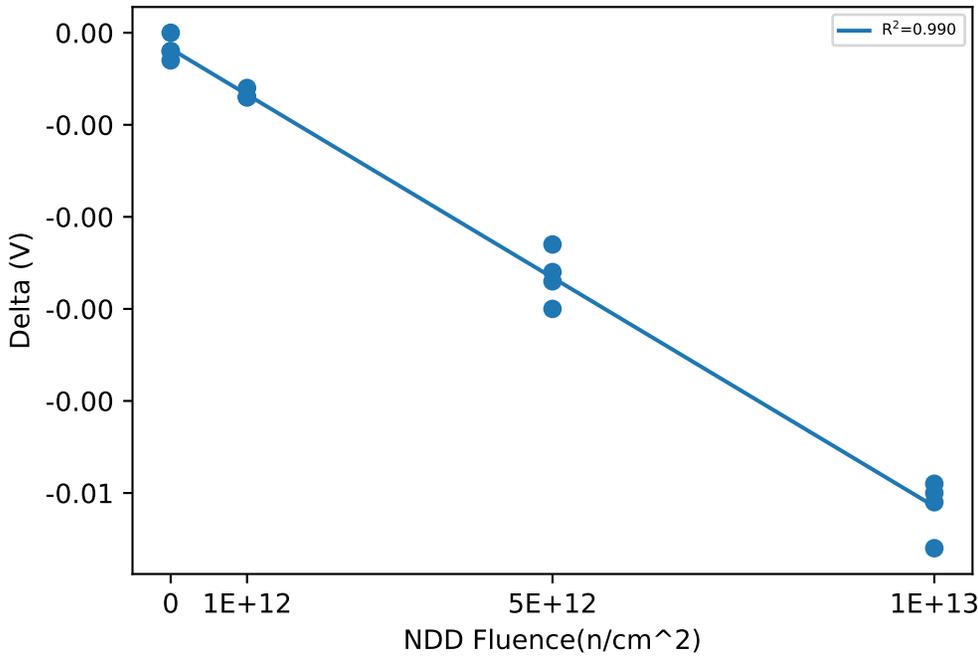

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

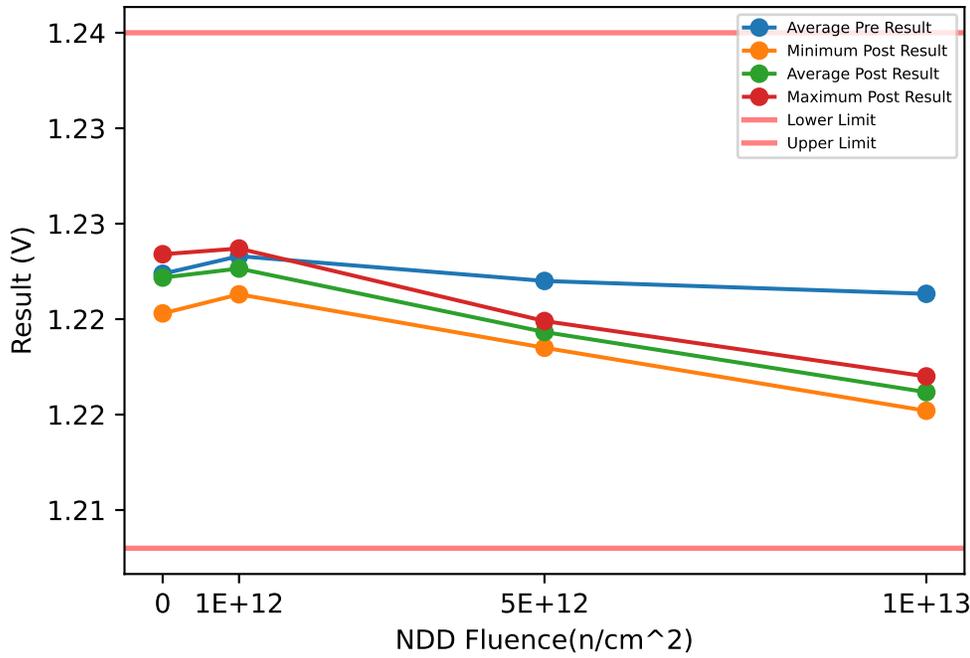| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.2235	1.2228	-0.0007
2	1e+12	NDD	1.2235	1.2228	-0.0007
3	1e+12	NDD	1.2219	1.2213	-0.0006
4	1e+12	NDD	1.2244	1.2237	-0.0007
5	5e+12	NDD	1.2216	1.219	-0.0026
6	5e+12	NDD	1.2229	1.2199	-0.003
7	5e+12	NDD	1.2208	1.2185	-0.0023
8	5e+12	NDD	1.2227	1.22	-0.0027
9	1e+13	NDD	1.2216	1.2166	-0.005
10	1e+13	NDD	1.2226	1.217	-0.0056
11	1e+13	NDD	1.22	1.2151	-0.0049
12	1e+13	NDD	1.221	1.2159	-0.0051
91	0	CORRELATION	1.2205	1.2203	-0.0002
92	0	CORRELATION	1.2234	1.2232	-0.0002
93	0	CORRELATION	1.2234	1.2234	0
94	0	CORRELATION	1.2223	1.222	-0.0003

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2205	1.2224	1.2234	0.0013687	1.2203	1.2222	1.2234	0.0014245	-0.0003	-0.000175	0	0.00012583
1e+12	1.2219	1.2233	1.2244	0.0010404	1.2213	1.2227	1.2237	0.00099499	-0.0007	-0.000675	-0.0006	5e-05
5e+12	1.2208	1.222	1.2229	0.00098319	1.2185	1.2193	1.22	0.00072342	-0.003	-0.00265	-0.0023	0.00028868
1e+13	1.22	1.2213	1.2226	0.0010893	1.2151	1.2162	1.217	0.00083467	-0.0056	-0.00515	-0.0049	0.00031091

# Device Test: 21.25 VOLTAGE|VREF/VREF/8/8/0/0/5/500kHz//@V_REFCAP

NDD vs Result Stats

Legend: Average Pre Result, Minimum Post Result, Average Post Result, Maximum Post Result, Lower Limit, Upper Limit

NDD vs Post - Pre Exposure Delta

$R^2=0.987$

Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.2235	1.2228	-0.0007
2	1e+12	NDD	1.2235	1.2228	-0.0007
3	1e+12	NDD	1.2218	1.2213	-0.0005
4	1e+12	NDD	1.2244	1.2237	-0.0007
5	5e+12	NDD	1.2216	1.219	-0.0026
6	5e+12	NDD	1.2229	1.2199	-0.003
7	5e+12	NDD	1.2208	1.2185	-0.0023
8	5e+12	NDD	1.2227	1.2199	-0.0028
9	1e+13	NDD	1.2216	1.2166	-0.005
10	1e+13	NDD	1.2227	1.217	-0.0057
11	1e+13	NDD	1.22	1.2152	-0.0048
12	1e+13	NDD	1.221	1.2159	-0.0051
91	0	CORRELATION	1.2205	1.2203	-0.0002
92	0	CORRELATION	1.2234	1.2231	-0.0003
93	0	CORRELATION	1.2234	1.2234	0
94	0	CORRELATION	1.2222	1.2219	-0.0003
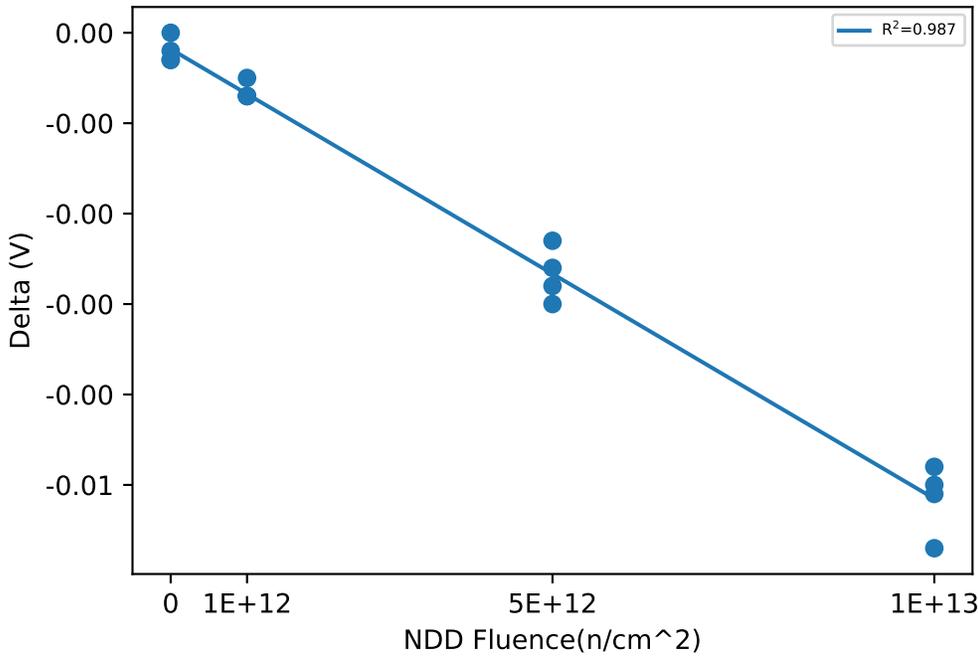
Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2205	1.2224	1.2234	0.001372	1.2203	1.2222	1.2234	0.001408	-0.0003	-0.0002	0	0.00014142
1e+12	1.2218	1.2233	1.2244	0.0010863	1.2213	1.2227	1.2237	0.00099499	-0.0007	-0.00065	-0.0005	0.0001
5e+12	1.2208	1.222	1.2229	0.00098319	1.2185	1.2193	1.2199	0.00069462	-0.003	-0.002675	-0.0023	0.00029861
1e+13	1.22	1.2213	1.2227	0.0011295	1.2152	1.2162	1.217	0.0007932	-0.0057	-0.00515	-0.0048	0.0003873

Device Test: 21.27 VOLTAGE|VREF/VREF/8/8/0/1000/5/100kHz//@V_REFCAP

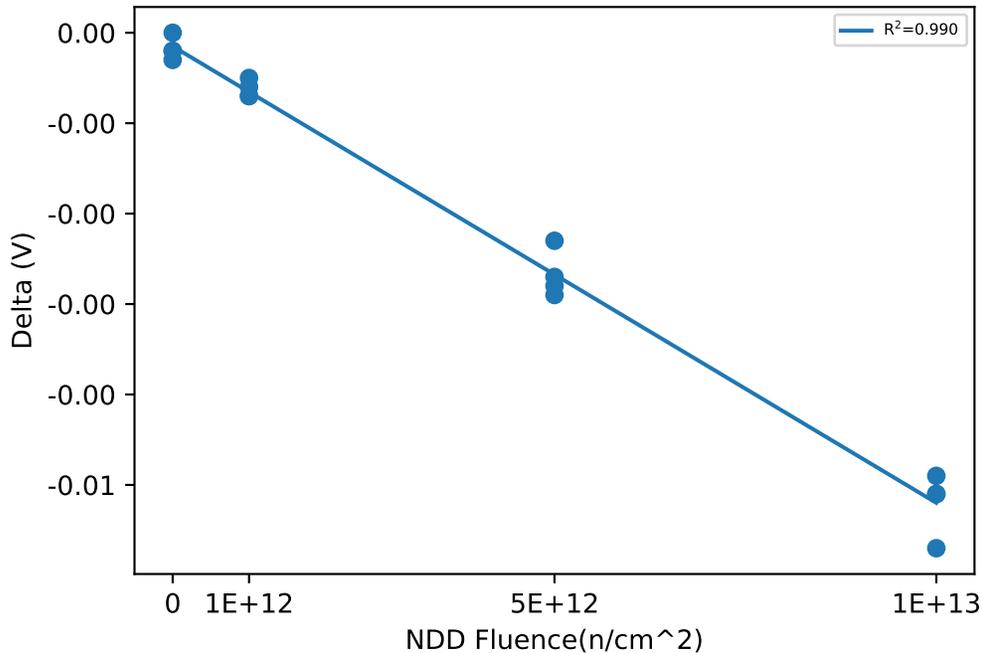## NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.2234	1.2228	-0.0006
2	1e+12	NDD	1.2235	1.2228	-0.0007
3	1e+12	NDD	1.2218	1.2213	-0.0005
4	1e+12	NDD	1.2244	1.2237	-0.0007
5	5e+12	NDD	1.2216	1.2189	-0.0027
6	5e+12	NDD	1.2229	1.22	-0.0029
7	5e+12	NDD	1.2208	1.2185	-0.0023
8	5e+12	NDD	1.2227	1.2199	-0.0028
9	1e+13	NDD	1.2217	1.2166	-0.0051
10	1e+13	NDD	1.2227	1.217	-0.0057
11	1e+13	NDD	1.22	1.2151	-0.0049
12	1e+13	NDD	1.221	1.2159	-0.0051
91	0	CORRELATION	1.2205	1.2203	-0.0002
92	0	CORRELATION	1.2234	1.2232	-0.0002
93	0	CORRELATION	1.2234	1.2234	0
94	0	CORRELATION	1.2223	1.222	-0.0003

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2205	1.2224	1.2234	0.0013687	1.2203	1.2222	1.2234	0.0014245	-0.0003	-0.000175	0	0.00012583
1e+12	1.2218	1.2233	1.2244	0.0010813	1.2213	1.2227	1.2237	0.00099499	-0.0007	-0.000625	-0.0005	9.5743e-05
5e+12	1.2208	1.222	1.2229	0.00098319	1.2185	1.2193	1.22	0.00074106	-0.0029	-0.002675	-0.0023	0.000263
1e+13	1.22	1.2213	1.2227	0.0011387	1.2151	1.2162	1.217	0.00083467	-0.0057	-0.0052	-0.0049	0.00034641
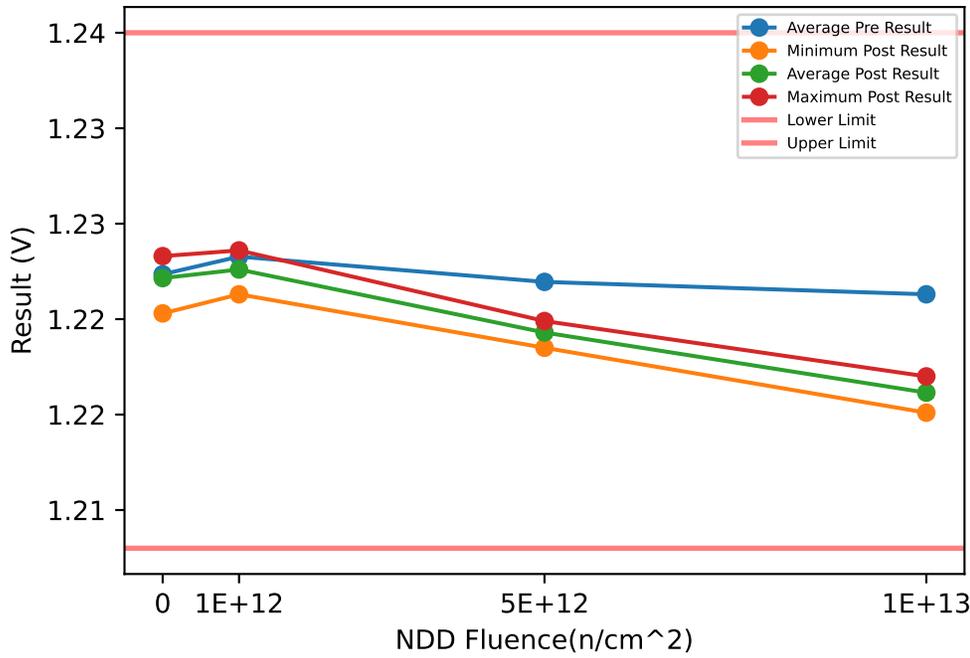
Device Test: 21.29 VOLTAGE|VREF/VREF/8/8/0/1000/5/500kHz//@V_REFCAP

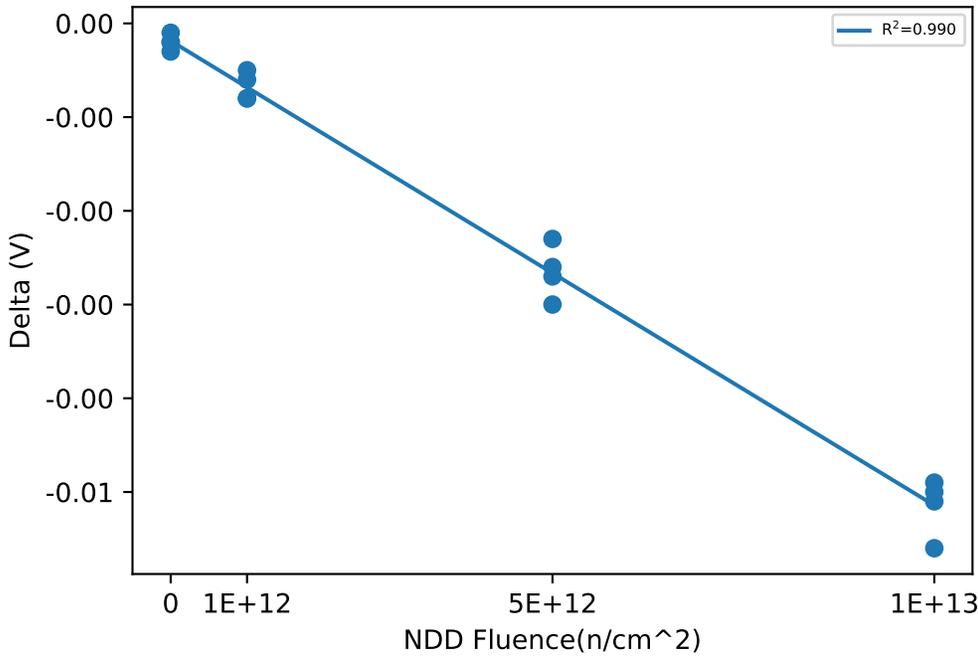## NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

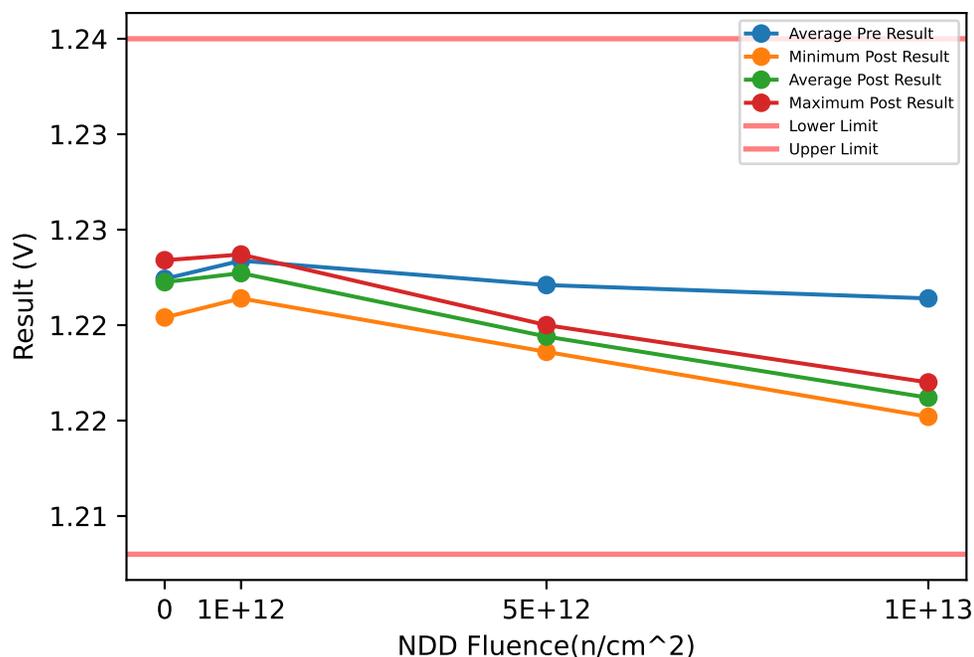| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.2234	1.2228	-0.0006
2	1e+12	NDD	1.2235	1.2227	-0.0008
3	1e+12	NDD	1.2218	1.2213	-0.0005
4	1e+12	NDD	1.2244	1.2236	-0.0008
5	5e+12	NDD	1.2215	1.2189	-0.0026
6	5e+12	NDD	1.2229	1.2199	-0.003
7	5e+12	NDD	1.2208	1.2185	-0.0023
8	5e+12	NDD	1.2226	1.2199	-0.0027
9	1e+13	NDD	1.2216	1.2166	-0.005
10	1e+13	NDD	1.2226	1.217	-0.0056
11	1e+13	NDD	1.22	1.2151	-0.0049
12	1e+13	NDD	1.221	1.2159	-0.0051
91	0	CORRELATION	1.2205	1.2203	-0.0002
92	0	CORRELATION	1.2233	1.2231	-0.0002
93	0	CORRELATION	1.2234	1.2233	-0.0001
94	0	CORRELATION	1.2222	1.2219	-0.0003

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2205	1.2224	1.2234	0.0013478	1.2203	1.2222	1.2233	0.0013796	-0.0003	-0.0002	-0.0001	8.165e-05
1e+12	1.2218	1.2233	1.2244	0.0010813	1.2213	1.2226	1.2236	0.00095568	-0.0008	-0.000675	-0.0005	0.00015
5e+12	1.2208	1.222	1.2229	0.00097468	1.2185	1.2193	1.2199	0.00071181	-0.003	-0.00265	-0.0023	0.00028868
1e+13	1.22	1.2213	1.2226	0.0010893	1.2151	1.2162	1.217	0.00083467	-0.0056	-0.00515	-0.0049	0.00031091

Device Test: 21.5 VOLTAGE|VREF/VREF/12/12/0/0/5/100kHz//@V_REFCAP

NDD vs Result Stats

Legend: Average Pre Result, Minimum Post Result, Average Post Result, Maximum Post Result, Lower Limit, Upper Limit

Y-axis: Result (V); X-axis: NDD Fluence(n/cm^2)

NDD vs Post - Pre Exposure Delta
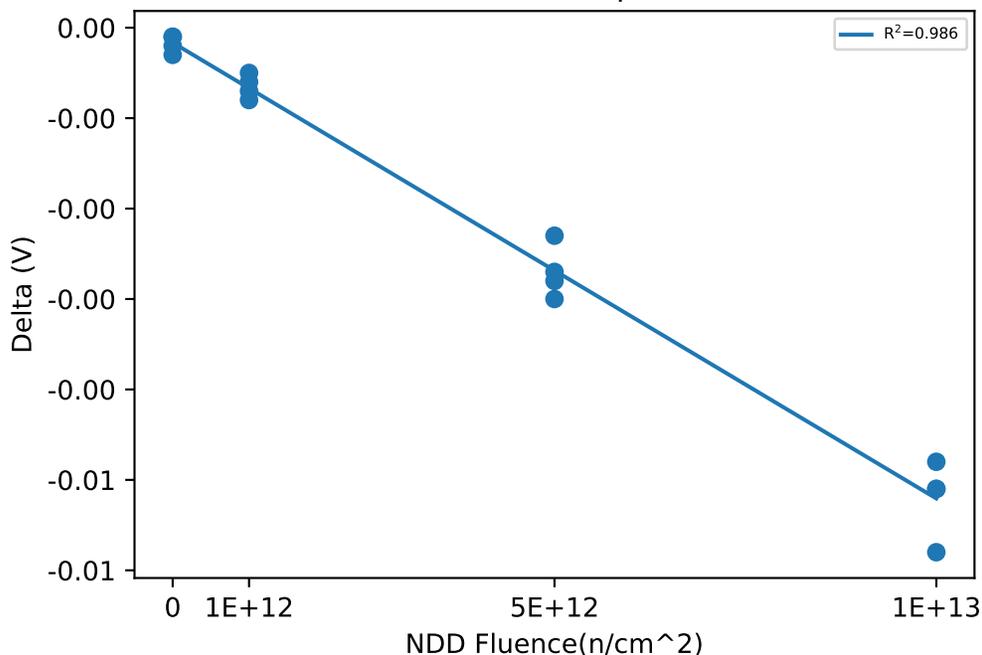
R²=0.986

Y-axis: Delta (V); X-axis: NDD Fluence(n/cm^2)

Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.2235	1.2229	-0.0006
2	1e+12	NDD	1.2236	1.2229	-0.0007
3	1e+12	NDD	1.2219	1.2214	-0.0005
4	1e+12	NDD	1.2245	1.2237	-0.0008
5	5e+12	NDD	1.2217	1.219	-0.0027
6	5e+12	NDD	1.223	1.22	-0.003
7	5e+12	NDD	1.2209	1.2186	-0.0023
8	5e+12	NDD	1.2228	1.22	-0.0028
9	1e+13	NDD	1.2217	1.2166	-0.0051
10	1e+13	NDD	1.2228	1.217	-0.0058
11	1e+13	NDD	1.22	1.2152	-0.0048
12	1e+13	NDD	1.2211	1.216	-0.0051
91	0	CORRELATION	1.2205	1.2204	-0.0001
92	0	CORRELATION	1.2234	1.2232	-0.0002
93	0	CORRELATION	1.2235	1.2234	-0.0001
94	0	CORRELATION	1.2223	1.222	-0.0003

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2205	1.2224	1.2235	0.0013937	1.2204	1.2223	1.2234	0.0013796	-0.0003	-0.000175	-0.0001	9.5743e-05
1e+12	1.2219	1.2234	1.2245	0.0010813	1.2214	1.2227	1.2237	0.00096047	-0.0008	-0.00065	-0.0005	0.0001291
5e+12	1.2209	1.2221	1.223	0.00098319	1.2186	1.2194	1.22	0.00071181	-0.003	-0.0027	-0.0023	0.00029439
1e+13	1.22	1.2214	1.2228	0.001169	1.2152	1.2162	1.217	0.00078316	-0.0058	-0.0052	-0.0048	0.00042426
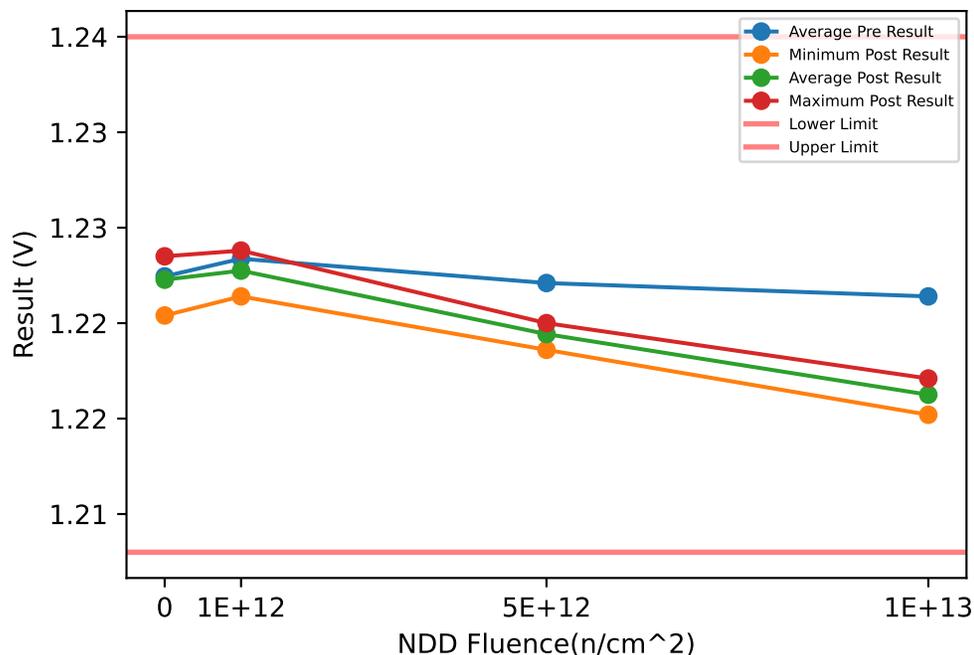
Device Test: 21.7 VOLTAGE|VREF/VREF/14/14/0/0/5/100kHz//@V_REFCAP

NDD vs Result Stats

Legend:
- Average Pre Result
- Minimum Post Result
- Average Post Result
- Maximum Post Result
- Lower Limit
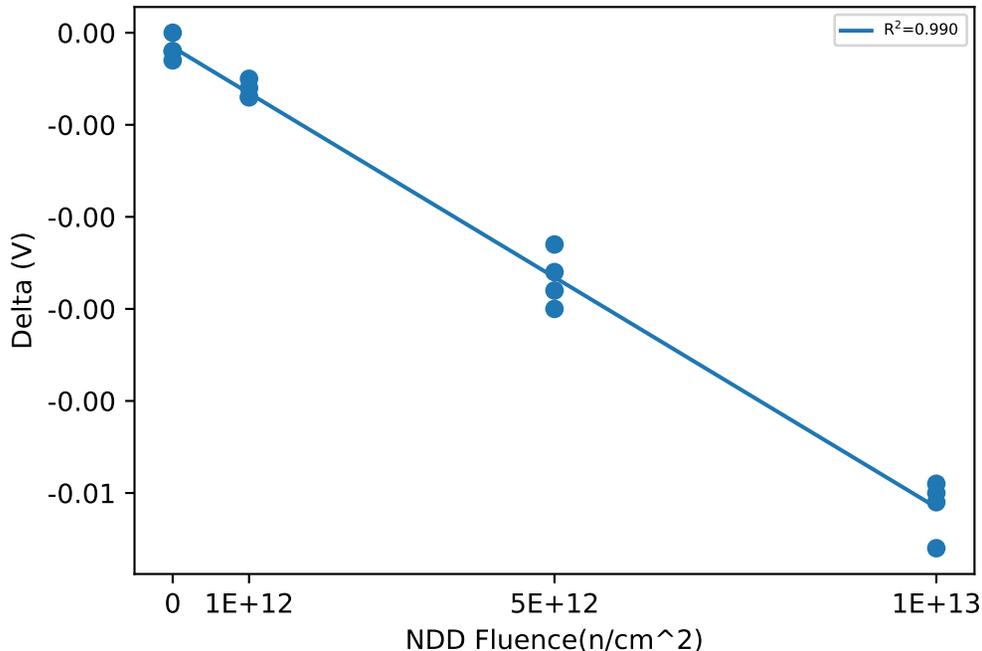- Upper Limit

NDD vs Post - Pre Exposure Delta

$R^2=0.990$

Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.2235	1.2229	-0.0006
2	1e+12	NDD	1.2236	1.2229	-0.0007
3	1e+12	NDD	1.2219	1.2214	-0.0005
4	1e+12	NDD	1.2245	1.2238	-0.0007
5	5e+12	NDD	1.2217	1.2191	-0.0026
6	5e+12	NDD	1.223	1.22	-0.003
7	5e+12	NDD	1.2209	1.2186	-0.0023
8	5e+12	NDD	1.2228	1.22	-0.0028
9	1e+13	NDD	1.2217	1.2167	-0.005
10	1e+13	NDD	1.2227	1.2171	-0.0056
11	1e+13	NDD	1.2201	1.2152	-0.0049
12	1e+13	NDD	1.2211	1.216	-0.0051
91	0	CORRELATION	1.2206	1.2204	-0.0002
92	0	CORRELATION	1.2234	1.2232	-0.0002
93	0	CORRELATION	1.2235	1.2235	0
94	0	CORRELATION	1.2223	1.222	-0.0003

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2206	1.2225	1.2235	0.0013478	1.2204	1.2223	1.2235	0.001408	-0.0003	-0.000175	0	0.00012583
1e+12	1.2219	1.2234	1.2245	0.0010813	1.2214	1.2228	1.2238	0.00099499	-0.0007	-0.000625	-0.0005	9.5743e-05
5e+12	1.2209	1.2221	1.223	0.00098319	1.2186	1.2194	1.22	0.00069462	-0.003	-0.002675	-0.0023	0.00029861
1e+13	1.2201	1.2214	1.2227	0.0010893	1.2152	1.2163	1.2171	0.00083467	-0.0056	-0.00515	-0.0049	0.00031091

Device Test: 21.9 VOLTAGE|VREF/VREF/12/12/0/0/5/500kHz//@V_REFCAP

NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.2235	1.2229	-0.0006
2	1e+12	NDD	1.2235	1.2228	-0.0007
3	1e+12	NDD	1.2219	1.2213	-0.0006
4	1e+12	NDD	1.2245	1.2237	-0.0008
5	5e+12	NDD	1.2216	1.219	-0.0026
6	5e+12	NDD	1.2229	1.22	-0.0029
7	5e+12	NDD	1.2208	1.2185	-0.0023
8	5e+12	NDD	1.2227	1.22	-0.0027
9	1e+13	NDD	1.2217	1.2166	-0.0051
10	1e+13	NDD	1.2227	1.217	-0.0057
11	1e+13	NDD	1.22	1.2152	-0.0048
12	1e+13	NDD	1.221	1.216	-0.005
91	0	CORRELATION	1.2205	1.2204	-0.0001
92	0	CORRELATION	1.2234	1.2232	-0.0002
93	0	CORRELATION	1.2234	1.2234	0
94	0	CORRELATION	1.2223	1.222	-0.0003
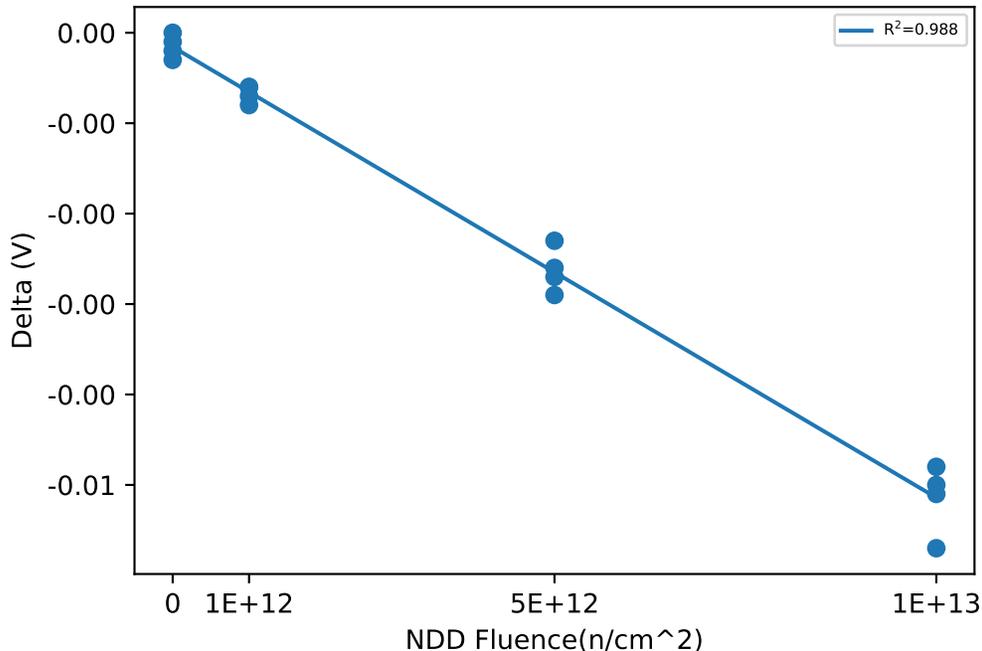
Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2205	1.2224	1.2234	0.0013687	1.2204	1.2223	1.2234	0.0013796	-0.0003	-0.00015	0	0.0001291
1e+12	1.2219	1.2233	1.2245	0.0010755	1.2213	1.2227	1.2237	0.0010012	-0.0008	-0.000675	-0.0006	9.5743e-05
5e+12	1.2208	1.222	1.2229	0.00098319	1.2185	1.2194	1.22	0.00075	-0.0029	-0.002625	-0.0023	0.00025
1e+13	1.22	1.2213	1.2227	0.0011387	1.2152	1.2162	1.217	0.00078316	-0.0057	-0.00515	-0.0048	0.0003873
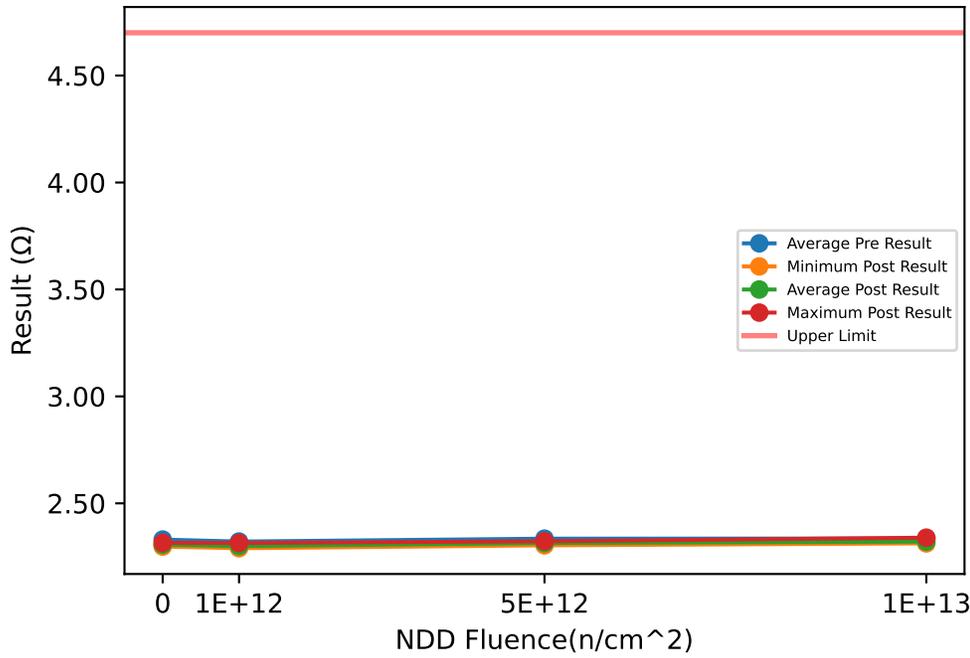
Device Test: 23.19 LEVEL|HS_RDSON/OUTH/12/12/100/0/5/500kHz//@ROH

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 4.7 (Ω))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	2.3138	2.2974	-0.0164
2	1e+12	NDD	2.3161	2.2989	-0.0172
3	1e+12	NDD	2.3232	2.2901	-0.0331
4	1e+12	NDD	2.3322	2.3144	-0.0178
5	5e+12	NDD	2.3264	2.3212	-0.0052
6	5e+12	NDD	2.3361	2.3228	-0.0133
7	5e+12	NDD	2.3269	2.3036	-0.0233
8	5e+12	NDD	2.3498	2.3099	-0.0399
9	1e+13	NDD	2.3183	2.3128	-0.0055
10	1e+13	NDD	2.3257	2.3158	-0.0099
11	1e+13	NDD	2.3419	2.3167	-0.0252
12	1e+13	NDD	2.3561	2.3394	-0.0167
91	0	CORRELATION	2.3275	2.3154	-0.0121
92	0	CORRELATION	2.3267	2.2979	-0.0288
93	0	CORRELATION	2.3305	2.3035	-0.027
94	0	CORRELATION	2.3373	2.3123	-0.025
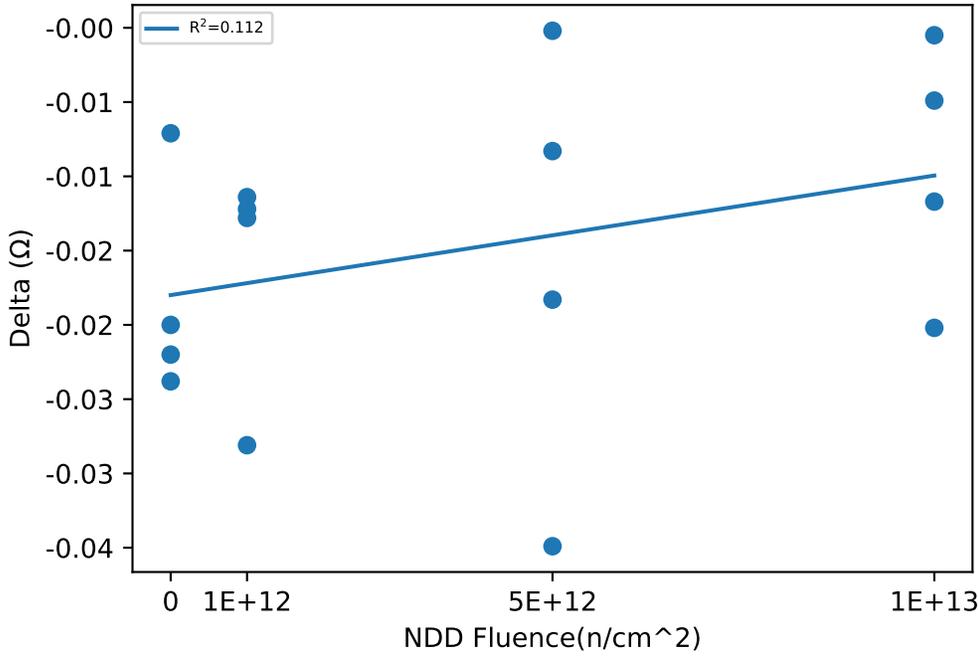
Test Statistics (Ω)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.3267	2.3305	2.3373	0.0048194	2.2979	2.3073	2.3154	0.0080293	-0.0288	-0.023225	-0.0121	0.0075773
1e+12	2.3138	2.3213	2.3322	0.0082807	2.2901	2.3002	2.3144	0.010217	-0.0331	-0.021125	-0.0164	0.0080039
5e+12	2.3264	2.3348	2.3498	0.010949	2.3036	2.3144	2.3228	0.0091958	-0.0399	-0.020425	-0.0052	0.014946
1e+13	2.3183	2.3355	2.3561	0.016904	2.3128	2.3212	2.3394	0.012264	-0.0252	-0.014325	-0.0055	0.0085901
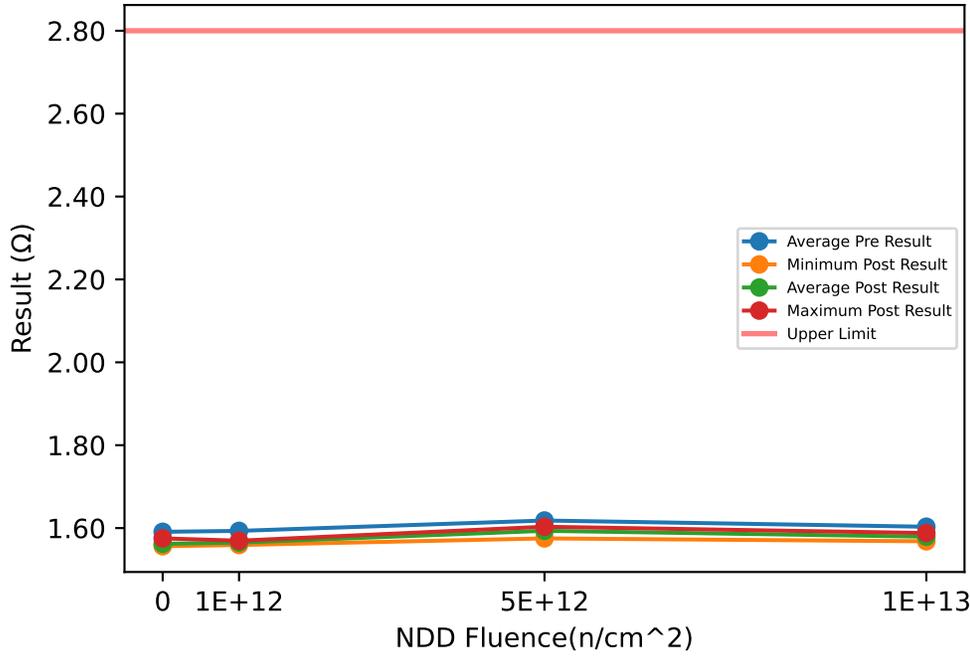
Device Test: 23.20 LEVEL|LS_RDSON/OUTL/12/12/100/0/5/500kHz//@ROL

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 2.8 (Ω))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.5961	1.5642	-0.0319
2	1e+12	NDD	1.5969	1.5695	-0.0274
3	1e+12	NDD	1.5895	1.5592	-0.0303
4	1e+12	NDD	1.5904	1.567	-0.0234
5	5e+12	NDD	1.6282	1.6032	-0.025
6	5e+12	NDD	1.6264	1.5969	-0.0295
7	5e+12	NDD	1.6004	1.5751	-0.0253
8	5e+12	NDD	1.6179	1.5984	-0.0195
9	1e+13	NDD	1.6076	1.5845	-0.0231
10	1e+13	NDD	1.6155	1.588	-0.0275
11	1e+13	NDD	1.6021	1.5761	-0.026
12	1e+13	NDD	1.5877	1.5681	-0.0196
91	0	CORRELATION	1.5898	1.5562	-0.0336
92	0	CORRELATION	1.5872	1.5589	-0.0283
93	0	CORRELATION	1.586	1.5582	-0.0278
94	0	CORRELATION	1.6009	1.5752	-0.0257
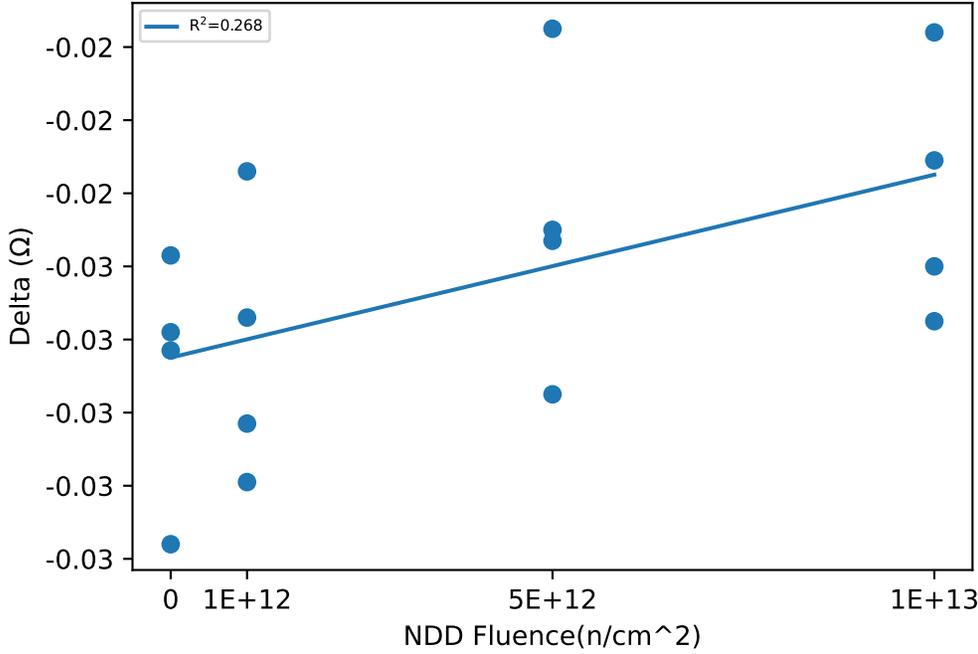
Test Statistics (Ω)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.586	1.591	1.6009	0.0068041	1.5562	1.5621	1.5752	0.0087914	-0.0336	-0.02885	-0.0257	0.0033611
1e+12	1.5895	1.5932	1.5969	0.0038135	1.5592	1.565	1.5695	0.0044169	-0.0319	-0.02825	-0.0234	0.0037314
5e+12	1.6004	1.6182	1.6282	0.012704	1.5751	1.5934	1.6032	0.012492	-0.0295	-0.024825	-0.0195	0.0041015
1e+13	1.5877	1.6032	1.6155	0.01172	1.5681	1.5792	1.588	0.0089134	-0.0275	-0.02405	-0.0196	0.0034838
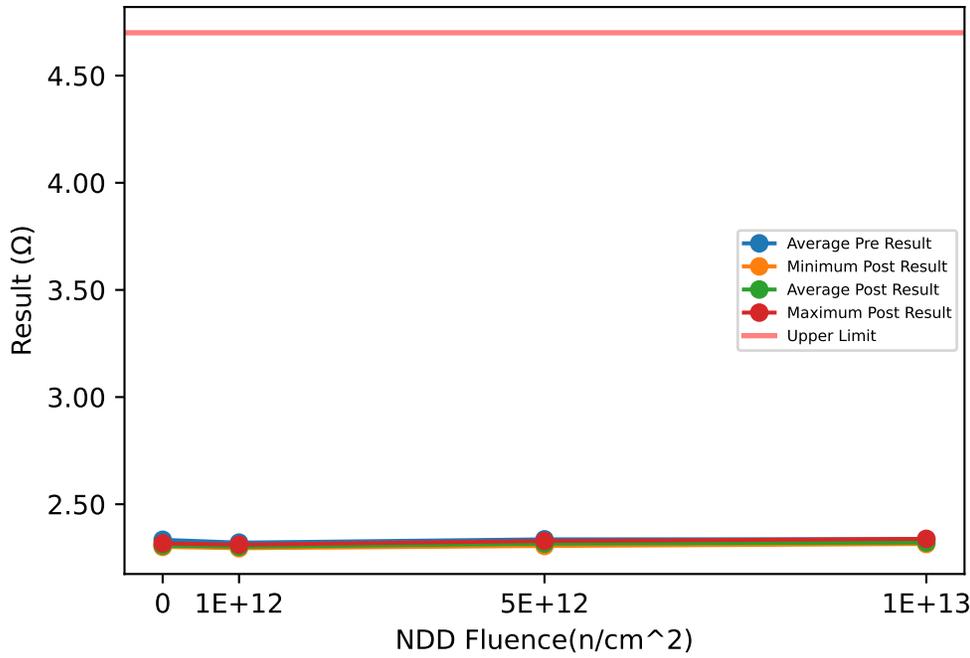
Device Test: 23.21 LEVEL|HS_RDSON/OUTH/14/14/100/0/5/500kHz//@ROH

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 4.7 (Ω))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	2.3094	2.2977	-0.0117
2	1e+12	NDD	2.3167	2.3028	-0.0139
3	1e+12	NDD	2.3214	2.2947	-0.0267
4	1e+12	NDD	2.3358	2.3112	-0.0246
5	5e+12	NDD	2.3252	2.3186	-0.0066
6	5e+12	NDD	2.3396	2.3285	-0.0111
7	5e+12	NDD	2.3291	2.3052	-0.0239
8	5e+12	NDD	2.3507	2.3119	-0.0388
9	1e+13	NDD	2.3215	2.3146	-0.0069
10	1e+13	NDD	2.3235	2.3144	-0.0091
11	1e+13	NDD	2.3417	2.3179	-0.0238
12	1e+13	NDD	2.3602	2.3384	-0.0218
91	0	CORRELATION	2.335	2.3173	-0.0177
92	0	CORRELATION	2.3273	2.3045	-0.0228
93	0	CORRELATION	2.332	2.3009	-0.0311
94	0	CORRELATION	2.3416	2.3073	-0.0343
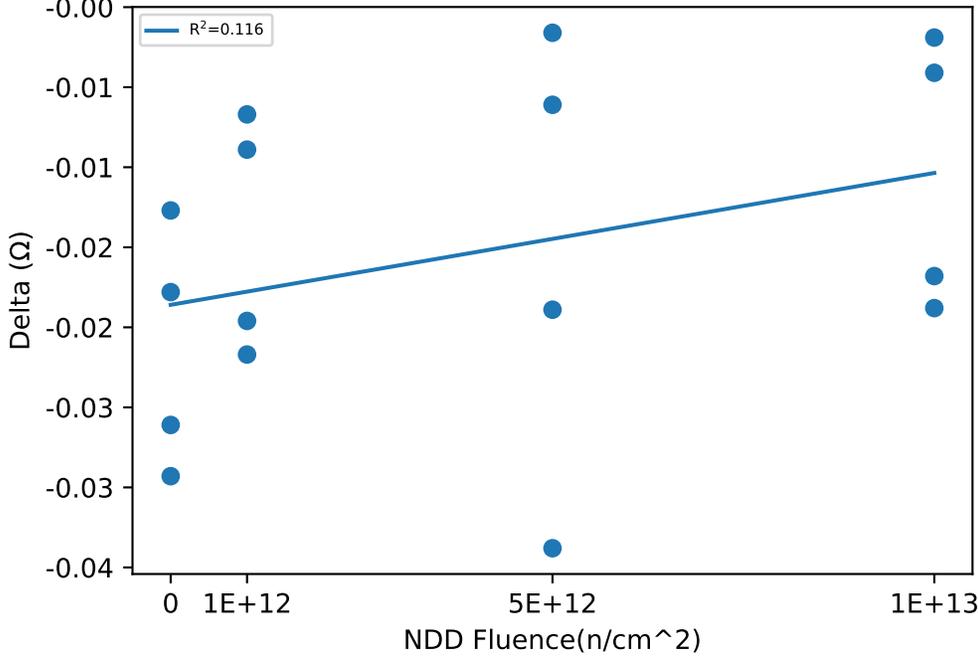
Test Statistics (Ω)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.3273	2.334	2.3416	0.0059902	2.3009	2.3075	2.3173	0.0070389	-0.0343	-0.026475	-0.0177	0.0075967
1e+12	2.3094	2.3208	2.3358	0.011137	2.2947	2.3016	2.3112	0.0072208	-0.0267	-0.019225	-0.0117	0.0075221
5e+12	2.3252	2.3361	2.3507	0.011449	2.3052	2.3161	2.3285	0.0099407	-0.0388	-0.0201	-0.0066	0.014461
1e+13	2.3215	2.3367	2.3602	0.018097	2.3144	2.3213	2.3384	0.011496	-0.0238	-0.0154	-0.0069	0.0086306
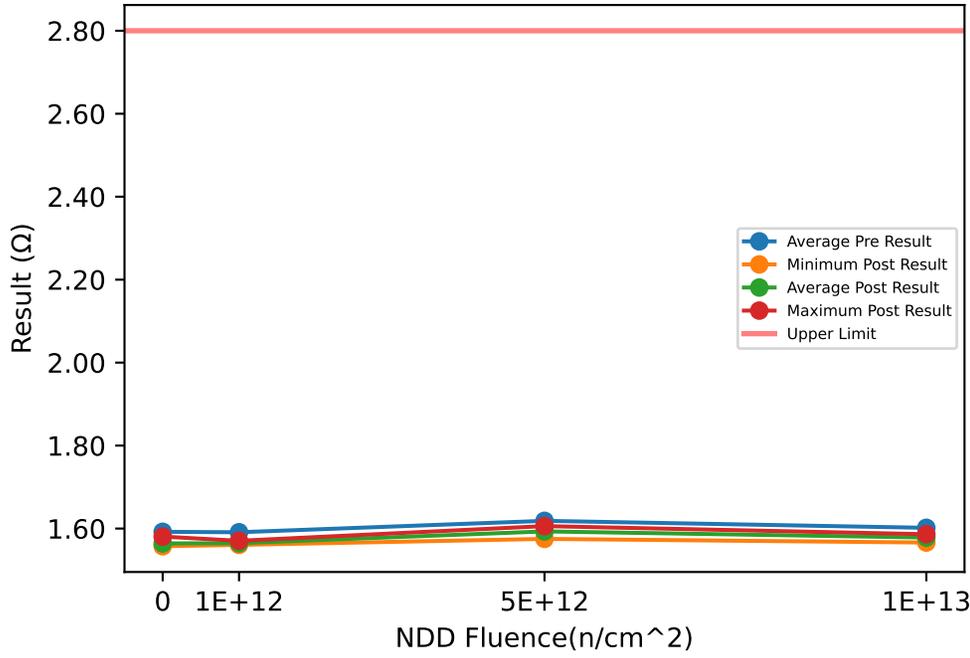
Device Test: 23.22 LEVEL|LS_RDSON/OUTL/14/14/100/0/5/500kHz//@ROL

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 2.8 (Ω))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.5908	1.5634	-0.0274
2	1e+12	NDD	1.5935	1.5705	-0.023
3	1e+12	NDD	1.5915	1.5607	-0.0308
4	1e+12	NDD	1.5885	1.5646	-0.0239
5	5e+12	NDD	1.6288	1.6059	-0.0229
6	5e+12	NDD	1.6272	1.5986	-0.0286
7	5e+12	NDD	1.6004	1.5751	-0.0253
8	5e+12	NDD	1.6179	1.5929	-0.025
9	1e+13	NDD	1.6102	1.5846	-0.0256
10	1e+13	NDD	1.6112	1.5863	-0.0249
11	1e+13	NDD	1.6005	1.5762	-0.0243
12	1e+13	NDD	1.5852	1.5663	-0.0189
91	0	CORRELATION	1.588	1.5598	-0.0282
92	0	CORRELATION	1.589	1.5588	-0.0302
93	0	CORRELATION	1.5879	1.5574	-0.0305
94	0	CORRELATION	1.6037	1.5806	-0.0231
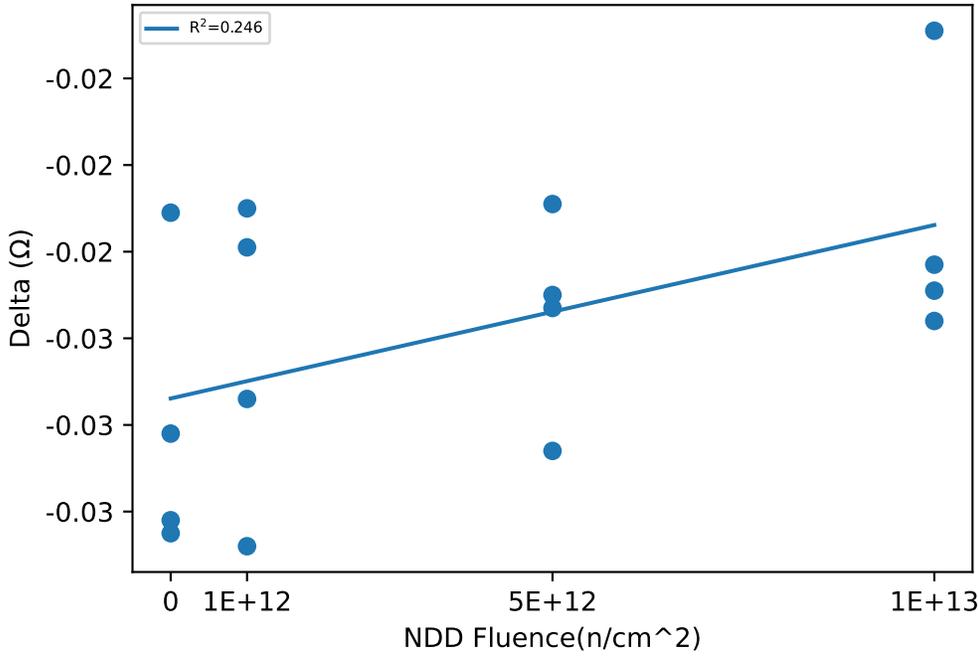
Test Statistics (Ω)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.5879	1.5921	1.6037	0.007716	1.5574	1.5641	1.5806	0.011011	-0.0305	-0.028	-0.0231	0.0034225
1e+12	1.5885	1.5911	1.5935	0.002063	1.5607	1.5648	1.5705	0.0041352	-0.0308	-0.026275	-0.023	0.0035641
5e+12	1.6004	1.6186	1.6288	0.013035	1.5751	1.5931	1.6059	0.013142	-0.0286	-0.02545	-0.0229	0.0023558
1e+13	1.5852	1.6018	1.6112	0.012058	1.5663	1.5783	1.5863	0.0091668	-0.0256	-0.023425	-0.0189	0.0030631
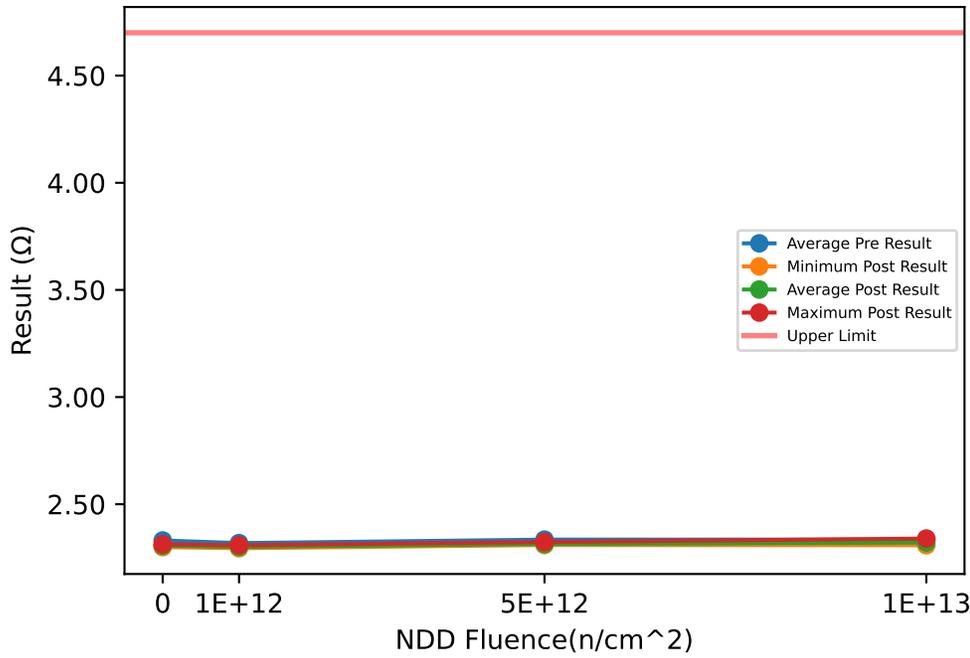
Device Test: 23.23 LEVEL|HS_RDSON/OUTH/12/12/500/0/5/500kHz//@ROH

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 4.7 (Ω))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	2.3097	2.2946	-0.0151
2	1e+12	NDD	2.3131	2.3026	-0.0105
3	1e+12	NDD	2.3167	2.2958	-0.0209
4	1e+12	NDD	2.3346	2.3085	-0.0261
5	5e+12	NDD	2.3258	2.3134	-0.0124
6	5e+12	NDD	2.3395	2.3236	-0.0159
7	5e+12	NDD	2.3254	2.3096	-0.0158
8	5e+12	NDD	2.3486	2.31	-0.0386
9	1e+13	NDD	2.3165	2.3085	-0.008
10	1e+13	NDD	2.326	2.3154	-0.0106
11	1e+13	NDD	2.3374	2.3209	-0.0165
12	1e+13	NDD	2.3602	2.3397	-0.0205
91	0	CORRELATION	2.3329	2.3128	-0.0201
92	0	CORRELATION	2.3241	2.2998	-0.0243
93	0	CORRELATION	2.3281	2.2999	-0.0282
94	0	CORRELATION	2.3388	2.311	-0.0278
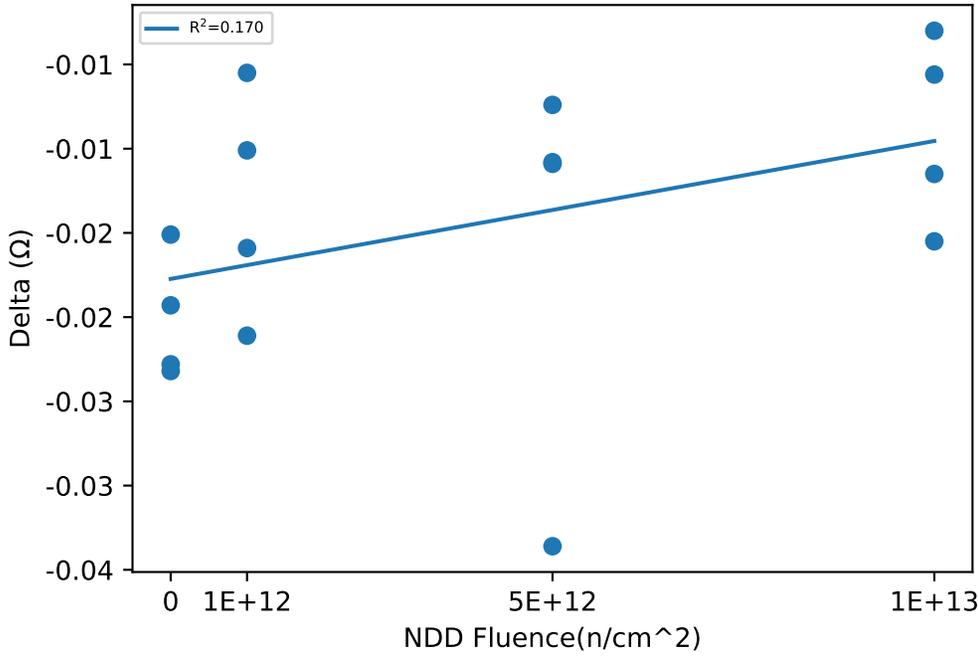
Test Statistics (Ω)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.3241	2.331	2.3388	0.0063369	2.2998	2.3059	2.3128	0.0069959	-0.0282	-0.0251	-0.0201	0.0037656
1e+12	2.3097	2.3185	2.3346	0.011091	2.2946	2.3004	2.3085	0.0064614	-0.0261	-0.01815	-0.0105	0.0067968
5e+12	2.3254	2.3348	2.3486	0.011283	2.3096	2.3142	2.3236	0.0065266	-0.0386	-0.020675	-0.0124	0.01206
1e+13	2.3165	2.335	2.3602	0.018833	2.3085	2.3211	2.3397	0.013382	-0.0205	-0.0139	-0.008	0.0056574
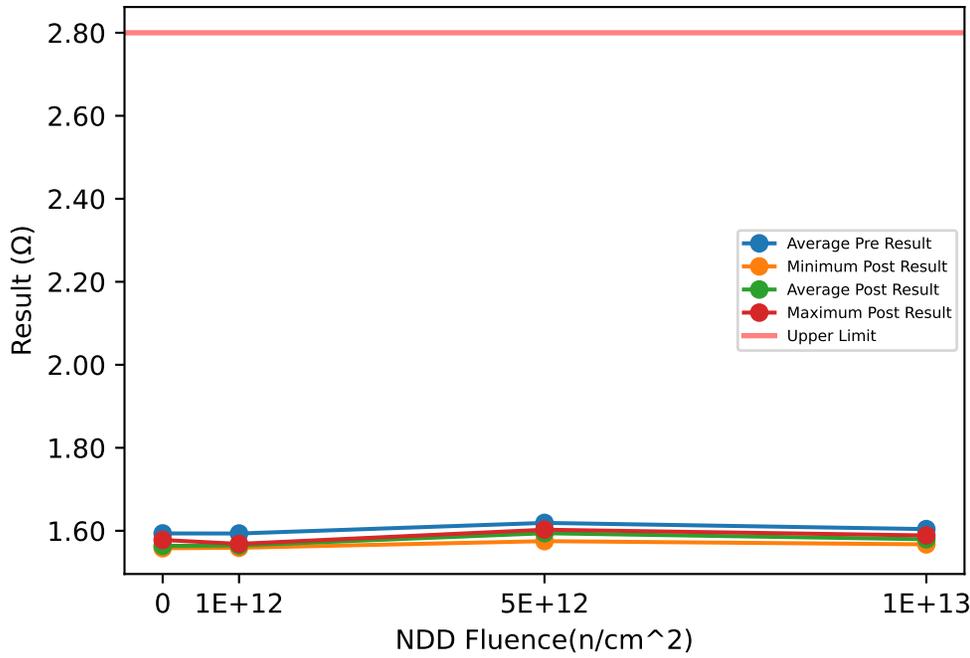
Device Test: 23.24 LEVEL|LS_RDSON/OUTL/12/12/500/0/5/500kHz//@ROL

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 2.8 (Ω))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.5934	1.5641	-0.0293
2	1e+12	NDD	1.5979	1.5685	-0.0294
3	1e+12	NDD	1.5905	1.5591	-0.0314
4	1e+12	NDD	1.5921	1.5663	-0.0258
5	5e+12	NDD	1.6297	1.6026	-0.0271
6	5e+12	NDD	1.6265	1.6015	-0.025
7	5e+12	NDD	1.5984	1.5751	-0.0233
8	5e+12	NDD	1.6215	1.5973	-0.0242
9	1e+13	NDD	1.6129	1.5855	-0.0274
10	1e+13	NDD	1.619	1.5888	-0.0302
11	1e+13	NDD	1.6002	1.5767	-0.0235
12	1e+13	NDD	1.5843	1.5673	-0.017
91	0	CORRELATION	1.5888	1.5598	-0.029
92	0	CORRELATION	1.589	1.558	-0.031
93	0	CORRELATION	1.5906	1.5592	-0.0314
94	0	CORRELATION	1.6062	1.5779	-0.0283
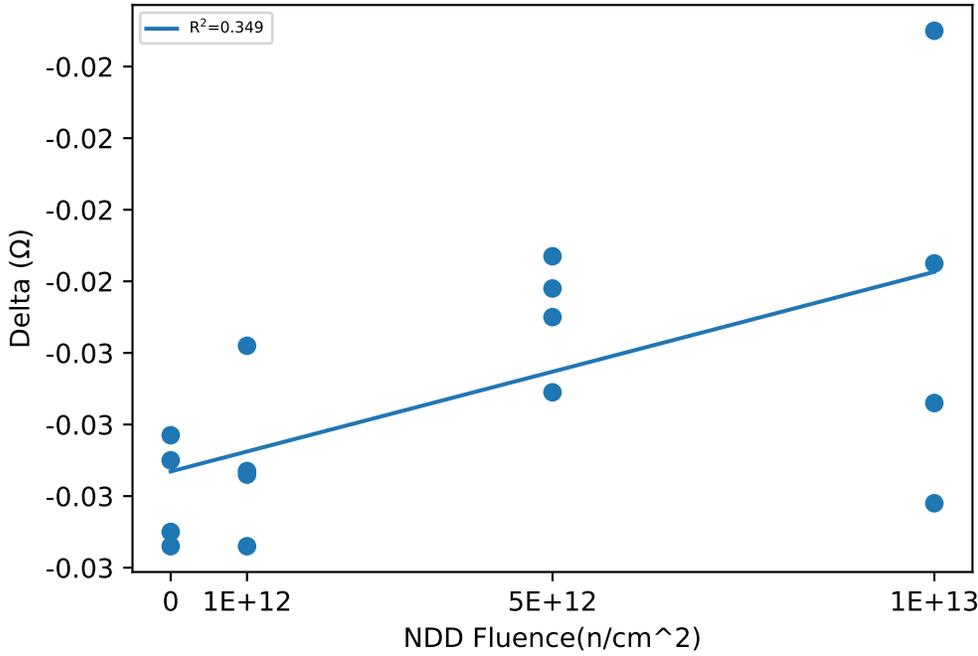
Test Statistics (Ω)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.5888	1.5937	1.6062	0.0084054	1.558	1.5637	1.5779	0.0094796	-0.0314	-0.029925	-0.0283	0.0015086
1e+12	1.5905	1.5935	1.5979	0.0031795	1.5591	1.5645	1.5685	0.0040233	-0.0314	-0.028975	-0.0258	0.0023272
5e+12	1.5984	1.619	1.6297	0.014158	1.5751	1.5941	1.6026	0.012887	-0.0271	-0.0249	-0.0233	0.0016228
1e+13	1.5843	1.6041	1.619	0.015348	1.5673	1.5796	1.5888	0.0096462	-0.0302	-0.024525	-0.017	0.0057198
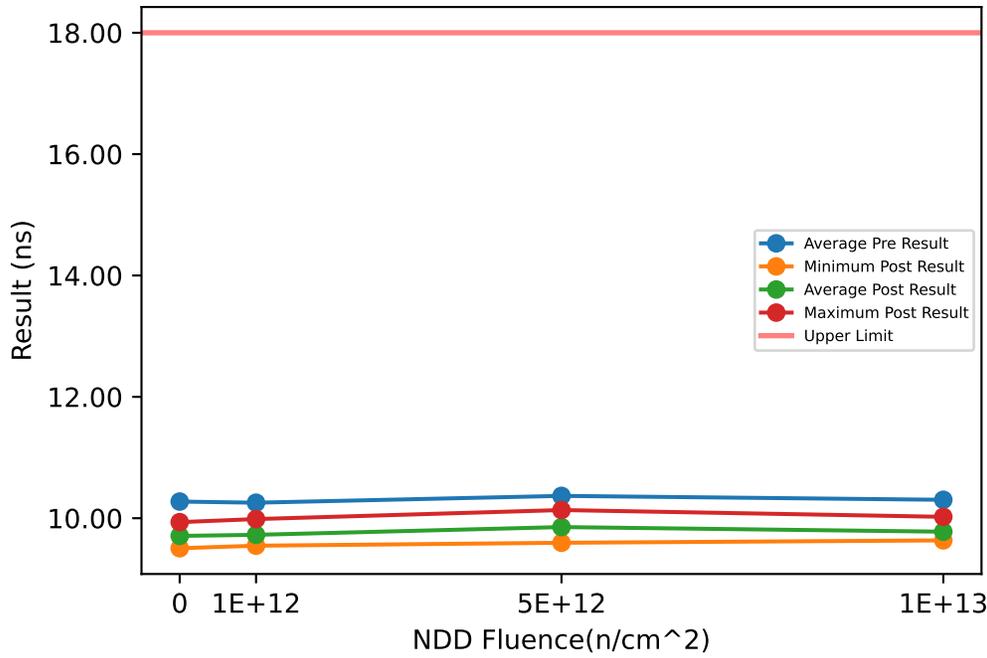
Device Test: 24.10 TIMING|OUT_FALL/OUTH/12/12/0/1000/5/500kHz//@OUT_FALL_12V

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 18.0 (ns))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	10.223	9.6946	-0.5288
2	1e+12	NDD	10.373	9.9858	-0.3877
3	1e+12	NDD	10.266	9.5469	-0.7187
4	1e+12	NDD	10.159	9.6772	-0.4818
5	5e+12	NDD	10.323	9.8708	-0.4526
6	5e+12	NDD	10.567	10.134	-0.4325
7	5e+12	NDD	10.269	9.5953	-0.6735
8	5e+12	NDD	10.312	9.8157	-0.4964
9	1e+13	NDD	10.282	9.7792	-0.5026
10	1e+13	NDD	10.433	10.023	-0.4097
11	1e+13	NDD	10.326	9.6347	-0.691
12	1e+13	NDD	10.174	9.675	-0.4987
91	0	CORRELATION	10.33	9.745	-0.5849
92	0	CORRELATION	10.371	9.9353	-0.4355
93	0	CORRELATION	10.215	9.5054	-0.7096
94	0	CORRELATION	10.182	9.6486	-0.5333
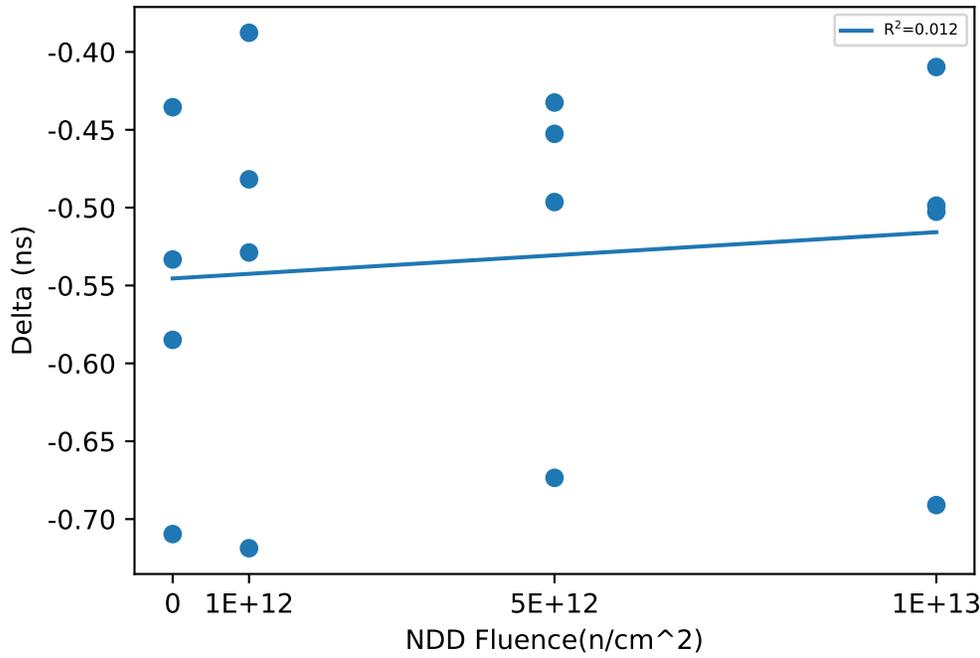
Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	10.182	10.274	10.371	0.090292	9.5054	9.7086	9.9353	0.18038	-0.7096	-0.56583	-0.4355	0.11413
1e+12	10.159	10.255	10.373	0.090127	9.5469	9.7261	9.9858	0.18524	-0.7187	-0.52925	-0.3877	0.13926
5e+12	10.269	10.368	10.567	0.13485	9.5953	9.8541	10.134	0.22163	-0.6735	-0.51375	-0.4325	0.10979
1e+13	10.174	10.303	10.433	0.1072	9.6347	9.778	10.023	0.17428	-0.691	-0.5255	-0.4097	0.11838

Device Test: 24.11 TIMING|OUT_RISE/OUTH/14/14/0/1000/5/500kHz//@OUT_RISE_14V

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 20.0 (ns))

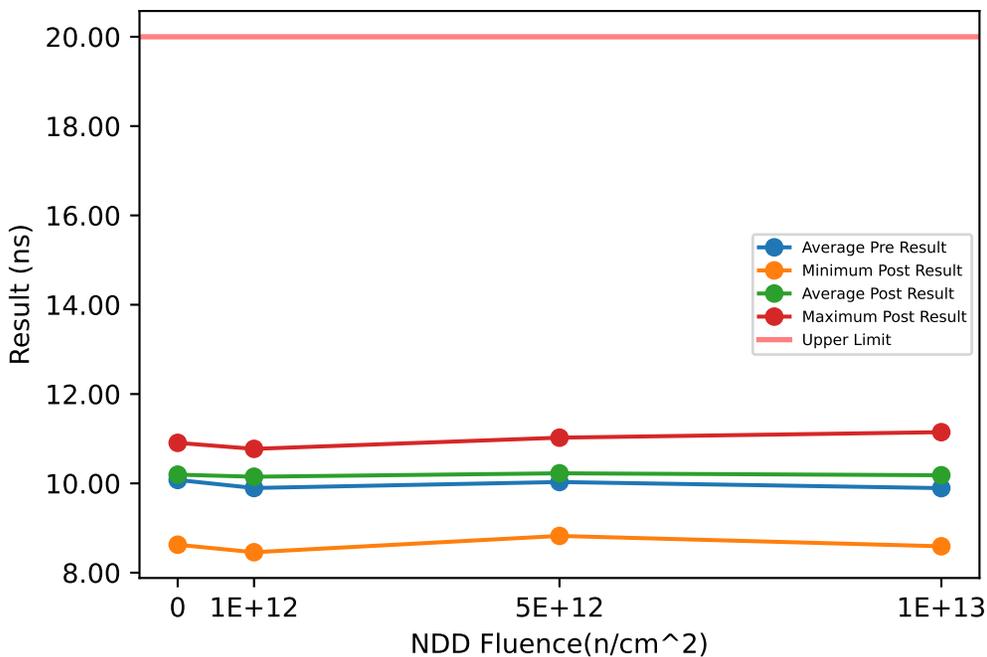| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	10.812	10.617	-0.195
2	1e+12	NDD	9.1699	8.4584	-0.7115
3	1e+12	NDD	8.9708	10.772	1.8016
4	1e+12	NDD	10.633	10.748	0.1155
5	5e+12	NDD	11.02	11.023	0.0032
6	5e+12	NDD	9.4257	8.8235	-0.6022
7	5e+12	NDD	8.9095	10.686	1.7762
8	5e+12	NDD	10.766	10.37	-0.3957
9	1e+13	NDD	10.57	10.879	0.3085
10	1e+13	NDD	9.2115	8.5912	-0.6203
11	1e+13	NDD	8.8855	11.147	2.2612
12	1e+13	NDD	10.908	10.11	-0.7979
91	0	CORRELATION	10.9	10.668	-0.2317
92	0	CORRELATION	9.325	8.6261	-0.6989
93	0	CORRELATION	9.0258	10.907	1.8815
94	0	CORRELATION	11.055	10.579	-0.476
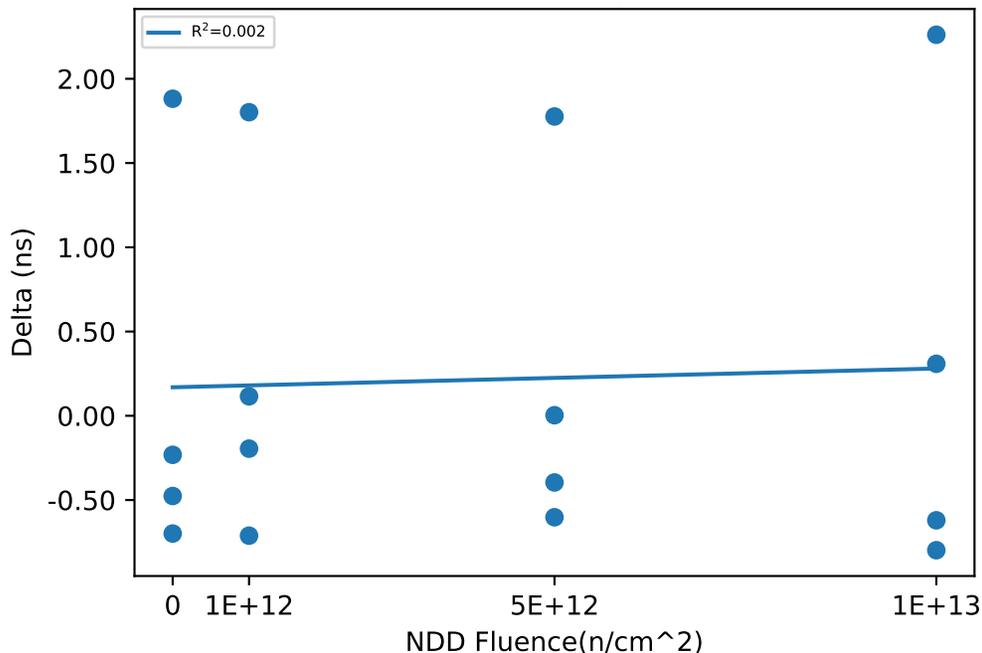
Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.0258	10.077	11.055	1.0496	8.6261	10.195	10.907	1.0552	-0.6989	0.11872	1.8815	1.1906
1e+12	8.9708	9.8963	10.812	0.95991	8.4584	10.149	10.772	1.1291	-0.7115	0.25265	1.8016	1.0875
5e+12	8.9095	10.03	11.02	1.0235	8.8235	10.226	11.023	0.9721	-0.6022	0.19537	1.7762	1.0834
1e+13	8.8855	9.8937	10.908	0.99452	8.5912	10.182	11.147	1.1477	-0.7979	0.28788	2.2612	1.4022
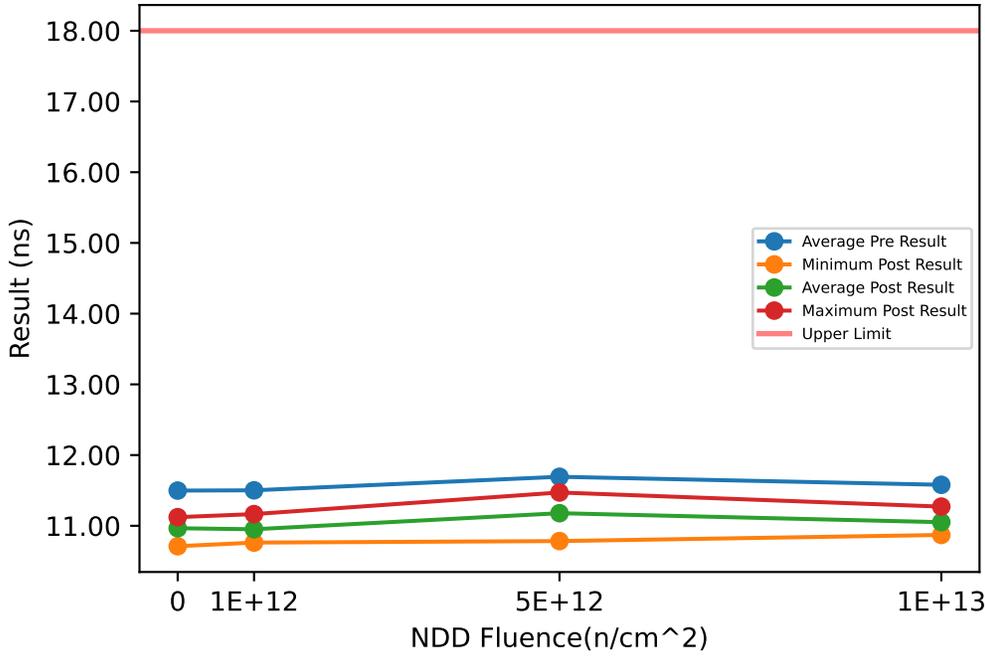
Device Test: 24.12 TIMING|OUT_FALL/OUTH/14/14/0/1000/5/500kHz//@OUT_FALL_14V

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 18.0 (ns))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	11.465	10.969	-0.4954
2	1e+12	NDD	11.568	11.165	-0.4026
3	1e+12	NDD	11.477	10.763	-0.7141
4	1e+12	NDD	11.497	10.907	-0.5902
5	5e+12	NDD	11.725	11.273	-0.4513
6	5e+12	NDD	11.877	11.471	-0.4064
7	5e+12	NDD	11.493	10.784	-0.709
8	5e+12	NDD	11.677	11.184	-0.4928
9	1e+13	NDD	11.57	11.109	-0.4615
10	1e+13	NDD	11.683	11.271	-0.4115
11	1e+13	NDD	11.577	10.87	-0.7061
12	1e+13	NDD	11.49	10.954	-0.5355
91	0	CORRELATION	11.62	11.122	-0.4977
92	0	CORRELATION	11.485	11.078	-0.407
93	0	CORRELATION	11.397	10.711	-0.6861
94	0	CORRELATION	11.489	10.951	-0.5382
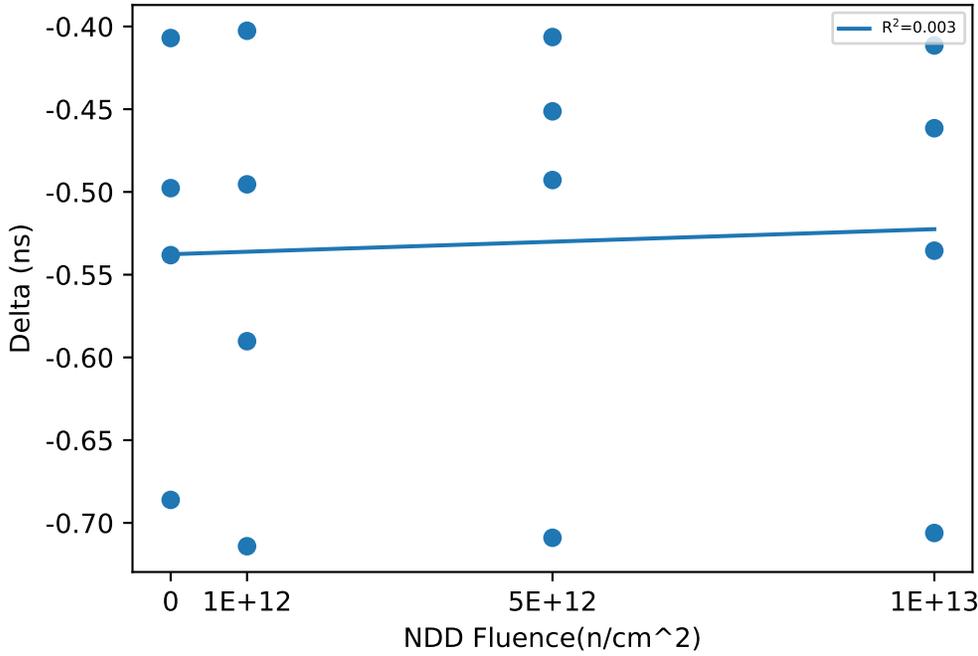
Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	11.397	11.498	11.62	0.091801	10.711	10.965	11.122	0.18444	-0.6861	-0.53225	-0.407	0.11631
1e+12	11.465	11.502	11.568	0.046257	10.763	10.951	11.165	0.16708	-0.7141	-0.55057	-0.4026	0.13323
5e+12	11.493	11.693	11.877	0.15839	10.784	11.178	11.471	0.28879	-0.709	-0.51487	-0.4064	0.13414
1e+13	11.49	11.58	11.683	0.07922	10.87	11.051	11.271	0.17685	-0.7061	-0.52865	-0.4115	0.1288

Device Test: 24.13 VOLTAGE|OUT_CLAMP/OUTL/0/0/0/0/0/0//@OUT_CLAMP_0V

NDD vs Result Stats

Legend:
- Average Pre Result
- Minimum Post Result
- Average Post Result
- Maximum Post Result
- Upper Limit

NDD vs Post - Pre Exposure Delta

$R^2=0.416$
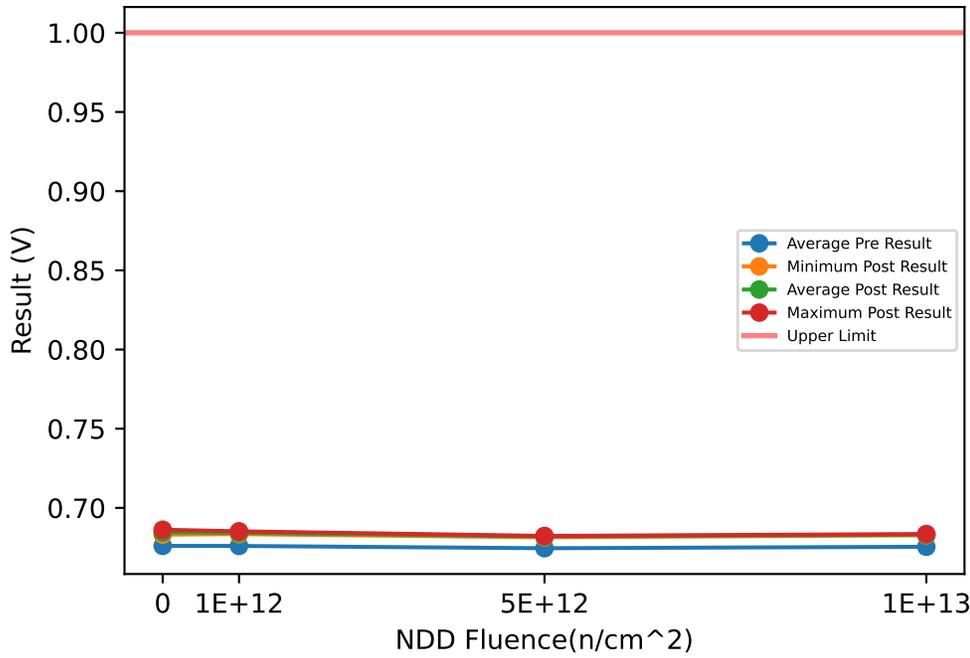
Test Results (Upper Limit = 1.0 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.675	0.6834	0.0084
2	1e+12	NDD	0.6752	0.6838	0.0086
3	1e+12	NDD	0.6765	0.6845	0.008
4	1e+12	NDD	0.6772	0.6852	0.008
5	5e+12	NDD	0.6748	0.6823	0.0075
6	5e+12	NDD	0.6745	0.6823	0.0078
7	5e+12	NDD	0.6743	0.6814	0.0071
8	5e+12	NDD	0.6745	0.6817	0.0072
9	1e+13	NDD	0.6749	0.6828	0.0079
10	1e+13	NDD	0.6753	0.6834	0.0081
11	1e+13	NDD	0.6761	0.6835	0.0074
12	1e+13	NDD	0.6755	0.6827	0.0072
91	0	CORRELATION	0.6774	0.6862	0.0088
92	0	CORRELATION	0.6764	0.6853	0.0089
93	0	CORRELATION	0.6749	0.6831	0.0082
94	0	CORRELATION	0.6753	0.6835	0.0082
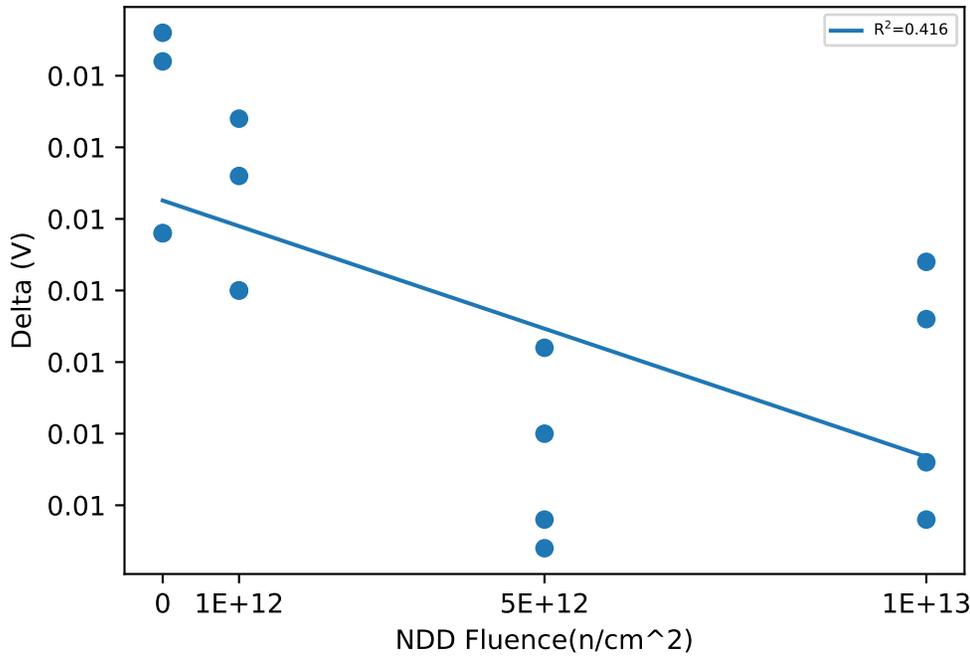
Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.6749	0.676	0.6774	0.0011284	0.6831	0.68453	0.6862	0.0014705	0.0082	0.008525	0.0089	0.00037749
1e+12	0.675	0.67597	0.6772	0.0010532	0.6834	0.68422	0.6852	0.0007932	0.008	0.00825	0.0086	0.0003
5e+12	0.6743	0.67453	0.6748	0.00020616	0.6814	0.68193	0.6823	0.00045	0.0071	0.0074	0.0078	0.00031623
1e+13	0.6749	0.67545	0.6761	0.0005	0.6827	0.6831	0.6835	0.00040825	0.0072	0.00765	0.0081	0.00042032

Device Test: 24.14 VOLTAGE|OUT_CLAMP/OUTL/5/0/0/0/0/0//@OUT_CLAMP_FULL

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 2.5 (V))

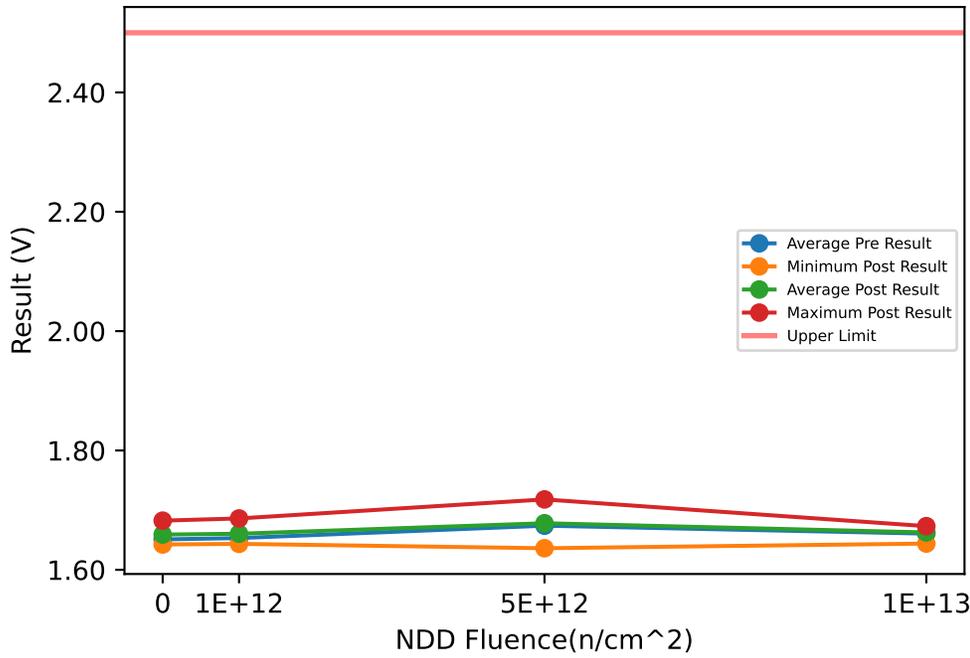| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.6364	1.6435	0.0071
2	1e+12	NDD	1.6581	1.6654	0.0073
3	1e+12	NDD	1.6785	1.6861	0.0076
4	1e+12	NDD	1.6398	1.6469	0.0071
5	5e+12	NDD	1.7137	1.718	0.0043
6	5e+12	NDD	1.6799	1.6837	0.0038
7	5e+12	NDD	1.6322	1.6362	0.004
8	5e+12	NDD	1.67	1.6744	0.0044
9	1e+13	NDD	1.6423	1.644	0.0017
10	1e+13	NDD	1.6712	1.6728	0.0016
11	1e+13	NDD	1.6587	1.6606	0.0019
12	1e+13	NDD	1.6705	1.6732	0.0027
91	0	CORRELATION	1.6552	1.6632	0.008
92	0	CORRELATION	1.6401	1.6482	0.0081
93	0	CORRELATION	1.6741	1.6824	0.0083
94	0	CORRELATION	1.6345	1.6425	0.008
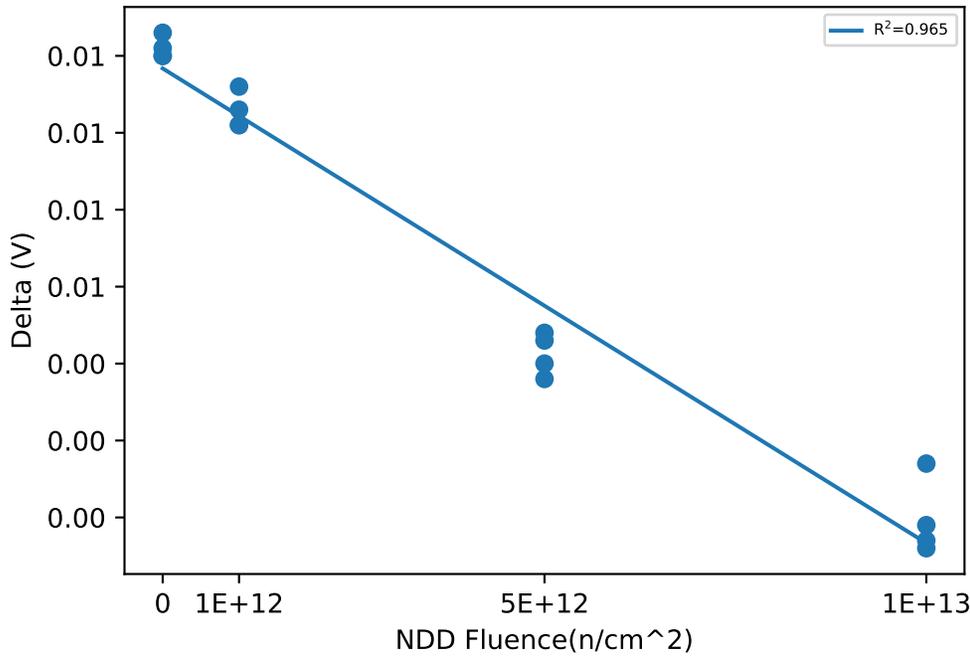
Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.6345	1.651	1.6741	0.017723	1.6425	1.6591	1.6824	0.017833	0.008	0.0081	0.0083	0.00014142
1e+12	1.6364	1.6532	1.6785	0.019373	1.6435	1.6605	1.6861	0.019607	0.0071	0.007275	0.0076	0.00023629
5e+12	1.6322	1.674	1.7137	0.033537	1.6362	1.6781	1.718	0.033629	0.0038	0.004125	0.0044	0.00027538
1e+13	1.6423	1.6607	1.6712	0.013526	1.644	1.6626	1.6732	0.01374	0.0016	0.001975	0.0027	0.00049917

Device Test: 24.15 LEVEL|LOW_LEVEL/OUTL/8/8/0/0/5/500kHz//@OUT_VOL

NDD vs Result Stats

Legend:
- Average Pre Result
- Minimum Post Result
- Average Post Result
- Maximum Post Result
- Upper Limit

NDD vs Post - Pre Exposure Delta

$R^2=0.190$

Test Results (Upper Limit = 0.15 (V))

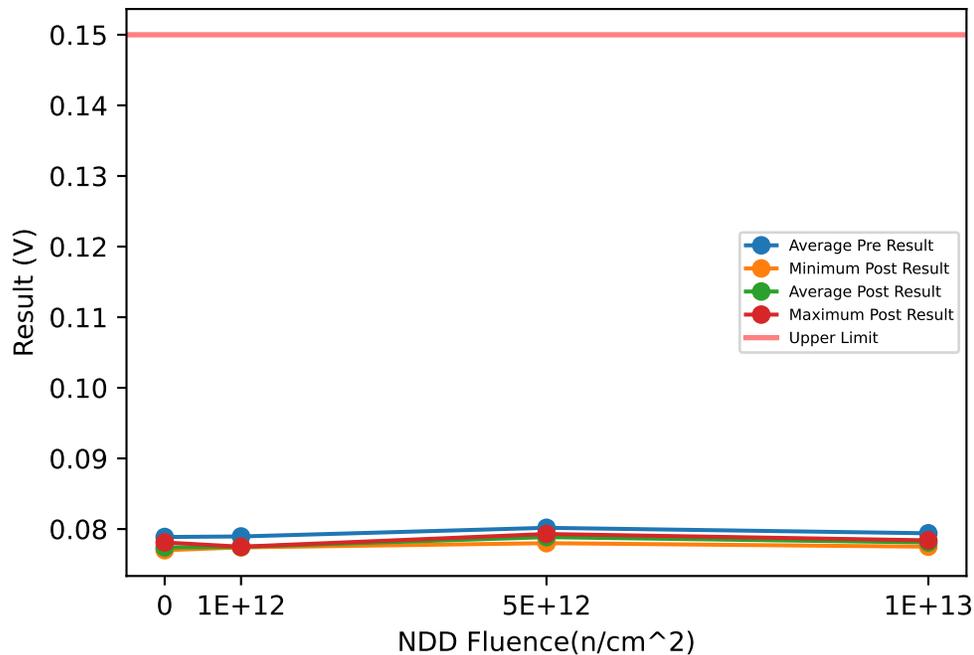| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.0788	0.0775	-0.0013
2	1e+12	NDD	0.0791	0.0775	-0.0016
3	1e+12	NDD	0.079	0.0774	-0.0016
4	1e+12	NDD	0.0789	0.0775	-0.0014
5	5e+12	NDD	0.0805	0.0793	-0.0012
6	5e+12	NDD	0.0804	0.0791	-0.0013
7	5e+12	NDD	0.0795	0.078	-0.0015
8	5e+12	NDD	0.0803	0.079	-0.0013
9	1e+13	NDD	0.0796	0.0784	-0.0012
10	1e+13	NDD	0.0799	0.0784	-0.0015
11	1e+13	NDD	0.0795	0.0781	-0.0014
12	1e+13	NDD	0.0786	0.0775	-0.0011
91	0	CORRELATION	0.0786	0.0773	-0.0013
92	0	CORRELATION	0.0785	0.077	-0.0015
93	0	CORRELATION	0.079	0.0772	-0.0018
94	0	CORRELATION	0.0794	0.0781	-0.0013
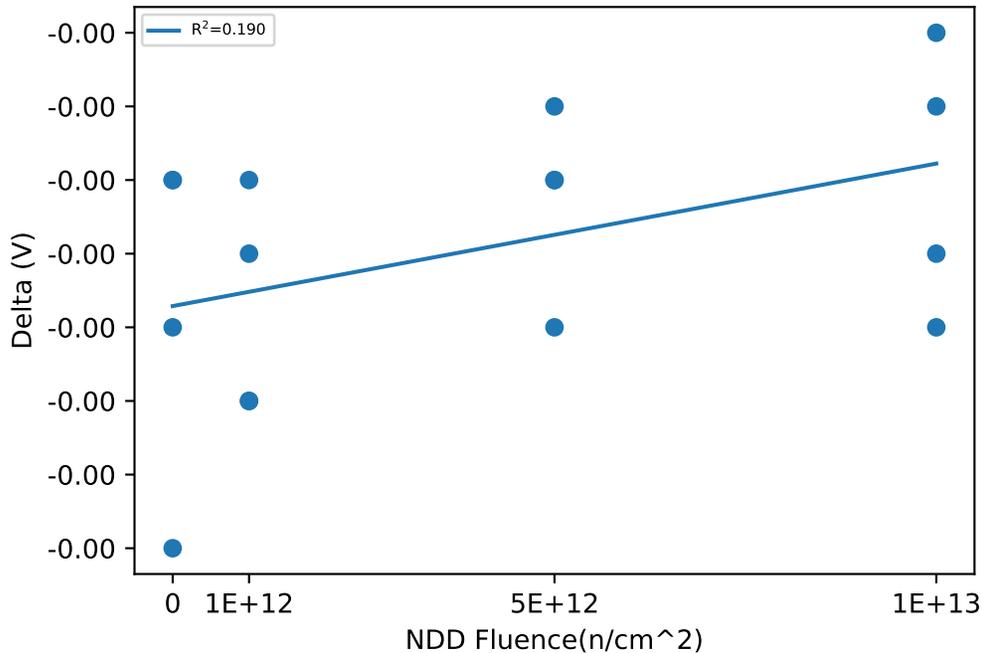
Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0785	0.078875	0.0794	0.0004113	0.077	0.0774	0.0781	0.00048305	-0.0018	-0.001475	-0.0013	0.00023629
1e+12	0.0788	0.07895	0.0791	0.0001291	0.0774	0.077475	0.0775	5e-05	-0.0016	-0.001475	-0.0013	0.00015
5e+12	0.0795	0.080175	0.0805	0.00045735	0.078	0.07885	0.0793	0.00058023	-0.0015	-0.001325	-0.0012	0.00012583
1e+13	0.0786	0.0794	0.0799	0.00055976	0.0775	0.0781	0.0784	0.00042426	-0.0015	-0.0013	-0.0011	0.00018257

Device Test: 24.16 LEVEL|HIGH_LEVEL/OUTH/8/8/0/0/5/500kHz//@OUT_VOH

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 0.25 (V))

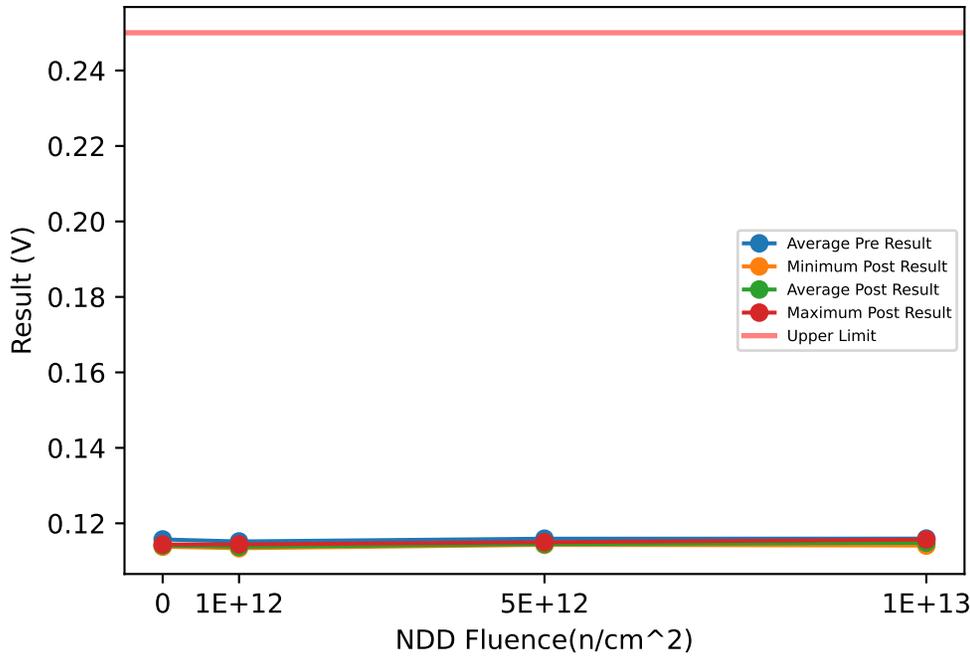| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.115	0.1134	-0.0016
2	1e+12	NDD	0.1151	0.1137	-0.0014
3	1e+12	NDD	0.1149	0.1136	-0.0013
4	1e+12	NDD	0.1158	0.1144	-0.0014
5	5e+12	NDD	0.1157	0.1143	-0.0014
6	5e+12	NDD	0.1162	0.115	-0.0012
7	5e+12	NDD	0.1155	0.1144	-0.0011
8	5e+12	NDD	0.1163	0.1143	-0.002
9	1e+13	NDD	0.1153	0.1141	-0.0012
10	1e+13	NDD	0.1157	0.1146	-0.0011
11	1e+13	NDD	0.1159	0.115	-0.0009
12	1e+13	NDD	0.1169	0.1157	-0.0012
91	0	CORRELATION	0.1159	0.1143	-0.0016
92	0	CORRELATION	0.1155	0.1138	-0.0017
93	0	CORRELATION	0.1155	0.114	-0.0015
94	0	CORRELATION	0.116	0.1144	-0.0016
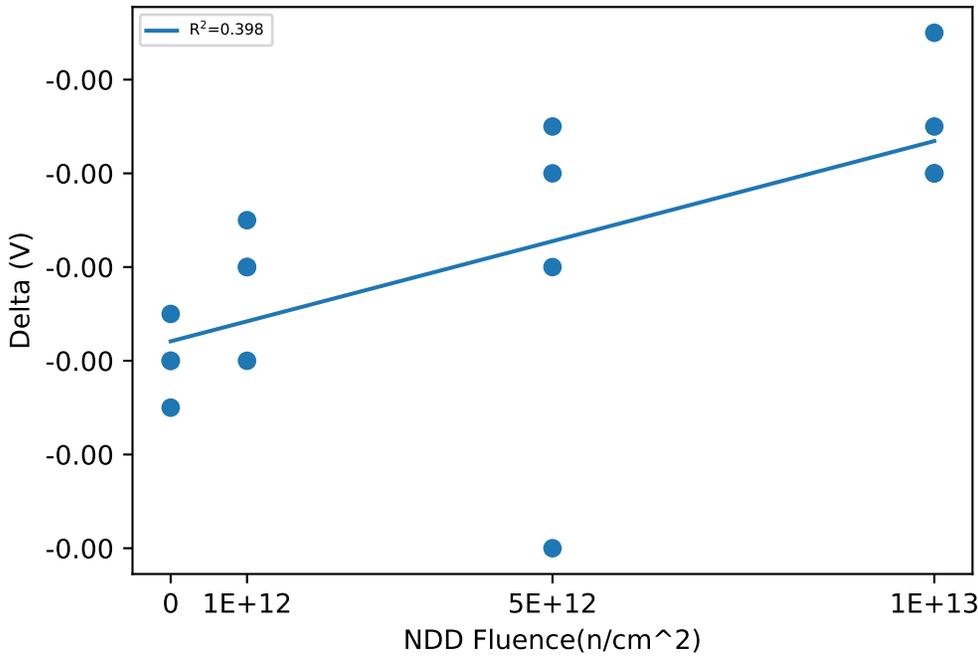
Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1155	0.11573	0.116	0.000263	0.1138	0.11413	0.1144	0.00027538	-0.0017	-0.0016	-0.0015	8.165e-05
1e+12	0.1149	0.1152	0.1158	0.00040825	0.1134	0.11378	0.1144	0.00043493	-0.0016	-0.001425	-0.0013	0.00012583
5e+12	0.1155	0.11593	0.1163	0.00038622	0.1143	0.1145	0.115	0.00033665	-0.002	-0.001425	-0.0011	0.00040311
1e+13	0.1153	0.11595	0.1169	0.00068069	0.1141	0.11485	0.1157	0.00067577	-0.0012	-0.0011	-0.0009	0.00014142

Device Test: 24.17 TIMING|OUT_RISE/OUTH/8/8/0/1000/4.5/500kHz//@OUT_RISE_8V

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 18.0 (ns))

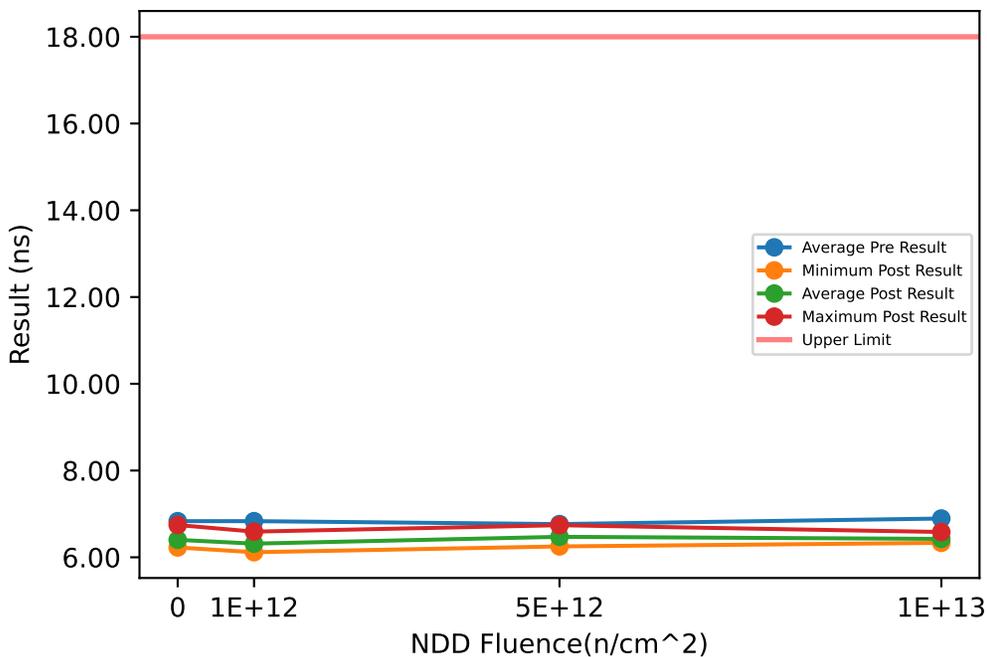| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	6.6516	6.5915	-0.0601
2	1e+12	NDD	6.7839	6.1168	-0.6671
3	1e+12	NDD	7.0008	6.2265	-0.7743
4	1e+12	NDD	6.8962	6.3247	-0.5715
5	5e+12	NDD	6.3005	6.7395	0.439
6	5e+12	NDD	6.8602	6.2506	-0.6096
7	5e+12	NDD	7.0493	6.3675	-0.6818
8	5e+12	NDD	6.8525	6.53	-0.3225
9	1e+13	NDD	6.7485	6.5831	-0.1654
10	1e+13	NDD	6.7698	6.3328	-0.437
11	1e+13	NDD	7.1117	6.3615	-0.7502
12	1e+13	NDD	6.9445	6.4203	-0.5242
91	0	CORRELATION	6.6529	6.7444	0.0915
92	0	CORRELATION	6.7986	6.3384	-0.4602
93	0	CORRELATION	6.9764	6.2995	-0.6769
94	0	CORRELATION	6.903	6.2269	-0.6761
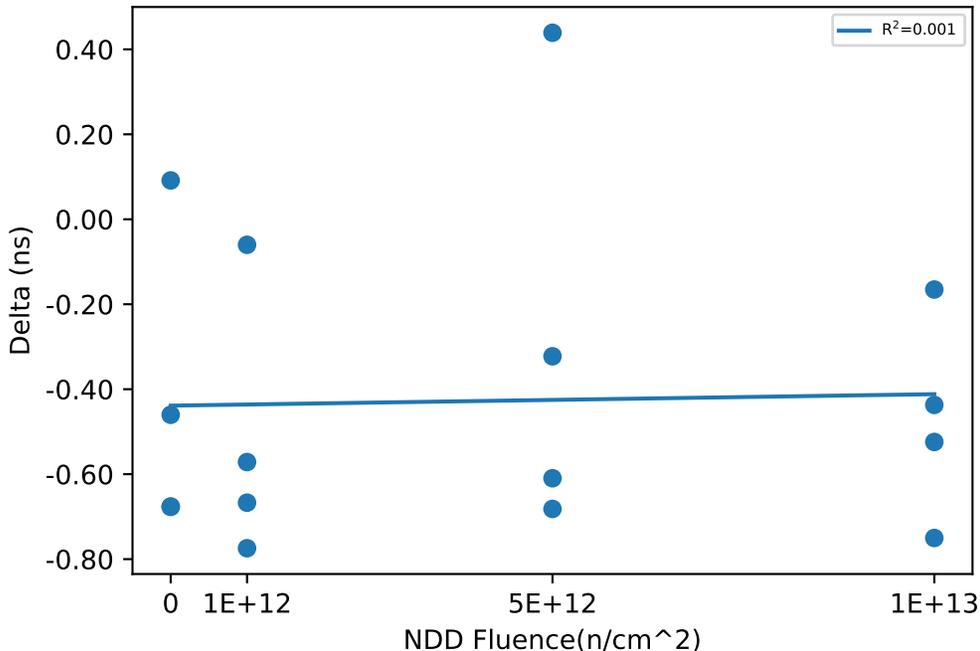
Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.6529	6.8327	6.9764	0.14034	6.2269	6.4023	6.7444	0.2327	-0.6769	-0.43043	0.0915	0.36258
1e+12	6.6516	6.8331	7.0008	0.14996	6.1168	6.3149	6.5915	0.20303	-0.7743	-0.51825	-0.0601	0.31647
5e+12	6.3005	6.7656	7.0493	0.32316	6.2506	6.4719	6.7395	0.21202	-0.6818	-0.29373	0.439	0.51254
1e+13	6.7485	6.8936	7.1117	0.16984	6.3328	6.4244	6.5831	0.11188	-0.7502	-0.4692	-0.1654	0.24174
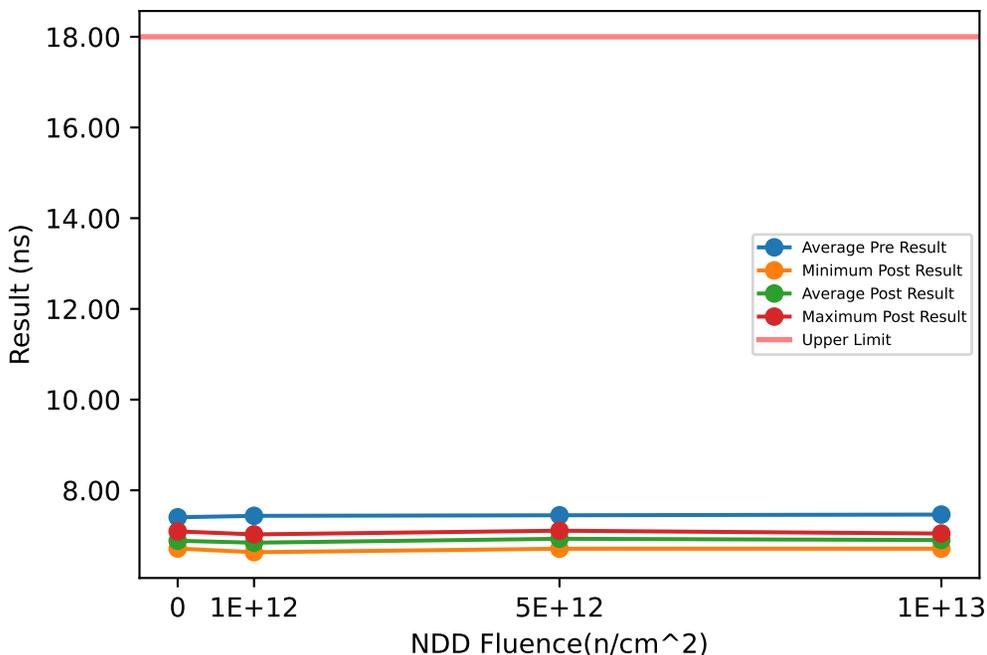
Device Test: 24.18 TIMING|OUT_FALL/OUTH/8/8/0/1000/4.5/500kHz//@OUT_FALL_8V

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 18.0 (ns))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	7.4102	6.8271	-0.5831
2	1e+12	NDD	7.356	6.8897	-0.4663
3	1e+12	NDD	7.404	6.6346	-0.7694
4	1e+12	NDD	7.5765	7.0277	-0.5488
5	5e+12	NDD	7.3888	6.9111	-0.4777
6	5e+12	NDD	7.3805	6.993	-0.3875
7	5e+12	NDD	7.4028	6.7115	-0.6913
8	5e+12	NDD	7.6247	7.1092	-0.5155
9	1e+13	NDD	7.4978	6.8915	-0.6063
10	1e+13	NDD	7.3868	6.9628	-0.424
11	1e+13	NDD	7.4249	6.7122	-0.7127
12	1e+13	NDD	7.5501	7.0461	-0.504
91	0	CORRELATION	7.3506	6.8337	-0.5169
92	0	CORRELATION	7.3328	6.9059	-0.4269
93	0	CORRELATION	7.3523	6.7164	-0.6359
94	0	CORRELATION	7.5846	7.0938	-0.4908
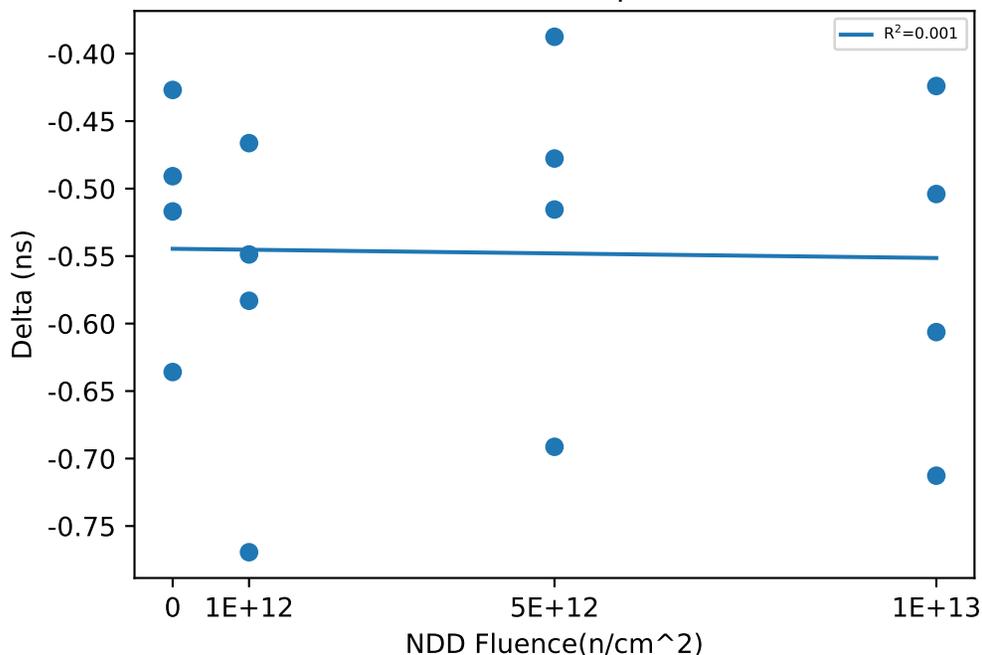
Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.3328	7.4051	7.5846	0.12001	6.7164	6.8875	7.0938	0.15819	-0.6359	-0.51762	-0.4269	0.087445
1e+12	7.356	7.4367	7.5765	0.096312	6.6346	6.8448	7.0277	0.16326	-0.7694	-0.5919	-0.4663	0.12808
5e+12	7.3805	7.4492	7.6247	0.11736	6.7115	6.9312	7.1092	0.16751	-0.6913	-0.518	-0.3875	0.1274
1e+13	7.3868	7.4649	7.5501	0.073123	6.7122	6.9032	7.0461	0.14212	-0.7127	-0.56175	-0.424	0.12527

Device Test: 24.5 LEVEL|LOW_LEVEL/OUTL/12/12/0/0/5/500kHz//@OUT_VOL

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 0.15 (V))

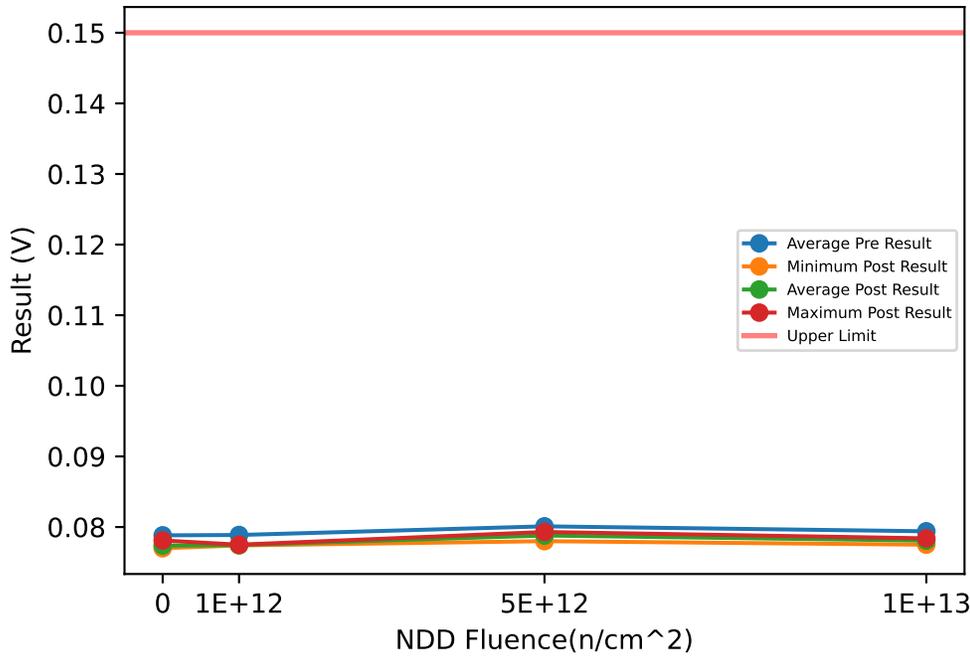| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.0787	0.0774	-0.0013
2	1e+12	NDD	0.079	0.0775	-0.0015
3	1e+12	NDD	0.079	0.0774	-0.0016
4	1e+12	NDD	0.0788	0.0775	-0.0013
5	5e+12	NDD	0.0804	0.0793	-0.0011
6	5e+12	NDD	0.0803	0.079	-0.0013
7	5e+12	NDD	0.0795	0.078	-0.0015
8	5e+12	NDD	0.0802	0.0789	-0.0013
9	1e+13	NDD	0.0796	0.0783	-0.0013
10	1e+13	NDD	0.0798	0.0784	-0.0014
11	1e+13	NDD	0.0796	0.0781	-0.0015
12	1e+13	NDD	0.0786	0.0775	-0.0011
91	0	CORRELATION	0.0785	0.0772	-0.0013
92	0	CORRELATION	0.0785	0.077	-0.0015
93	0	CORRELATION	0.0789	0.0772	-0.0017
94	0	CORRELATION	0.0794	0.0781	-0.0013
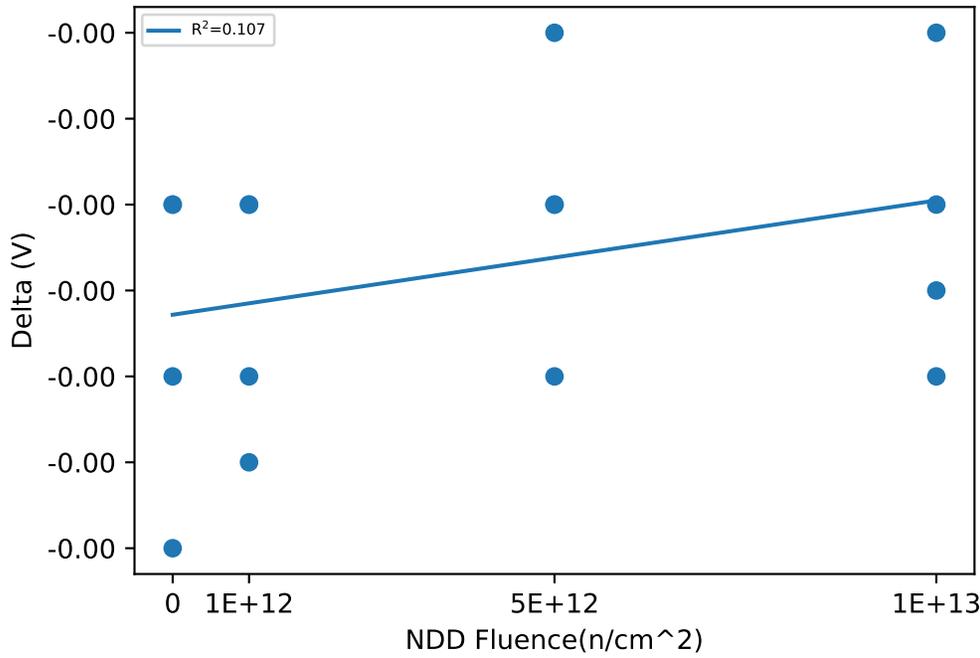
Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0785	0.078825	0.0794	0.0004272	0.077	0.077375	0.0781	0.00049244	-0.0017	-0.00145	-0.0013	0.00019149
1e+12	0.0787	0.078875	0.079	0.00015	0.0774	0.07745	0.0775	5.7735e-05	-0.0016	-0.001425	-0.0013	0.00015
5e+12	0.0795	0.0801	0.0804	0.00040825	0.078	0.0788	0.0793	0.00055976	-0.0015	-0.0013	-0.0011	0.0001633
1e+13	0.0786	0.0794	0.0798	0.0005416	0.0775	0.078075	0.0784	0.00040311	-0.0015	-0.001325	-0.0011	0.00017078

Device Test: 24.6 LEVEL|HIGH_LEVEL/OUTH/12/12/0/0/5/500kHz//@OUT_VOH

NDD vs Result Stats

Legend: Average Pre Result, Minimum Post Result, Average Post Result, Maximum Post Result, Upper Limit

NDD vs Post - Pre Exposure Delta

$R^2=0.432$

Test Results (Upper Limit = 0.25 (V))

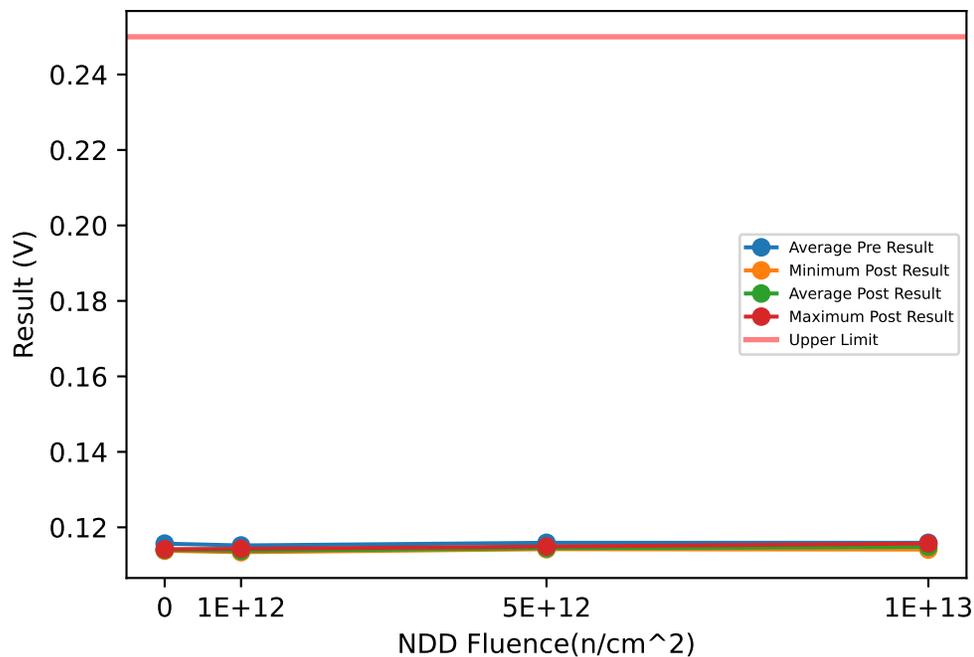| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.115	0.1134	-0.0016
2	1e+12	NDD	0.1151	0.1137	-0.0014
3	1e+12	NDD	0.1149	0.1136	-0.0013
4	1e+12	NDD	0.1158	0.1143	-0.0015
5	5e+12	NDD	0.1157	0.1144	-0.0013
6	5e+12	NDD	0.1162	0.1149	-0.0013
7	5e+12	NDD	0.1154	0.1143	-0.0011
8	5e+12	NDD	0.1163	0.1142	-0.0021
9	1e+13	NDD	0.1153	0.1141	-0.0012
10	1e+13	NDD	0.1156	0.1146	-0.001
11	1e+13	NDD	0.1159	0.1149	-0.001
12	1e+13	NDD	0.1168	0.1157	-0.0011
91	0	CORRELATION	0.1159	0.1142	-0.0017
92	0	CORRELATION	0.1155	0.1138	-0.0017
93	0	CORRELATION	0.1154	0.1139	-0.0015
94	0	CORRELATION	0.1159	0.1142	-0.0017
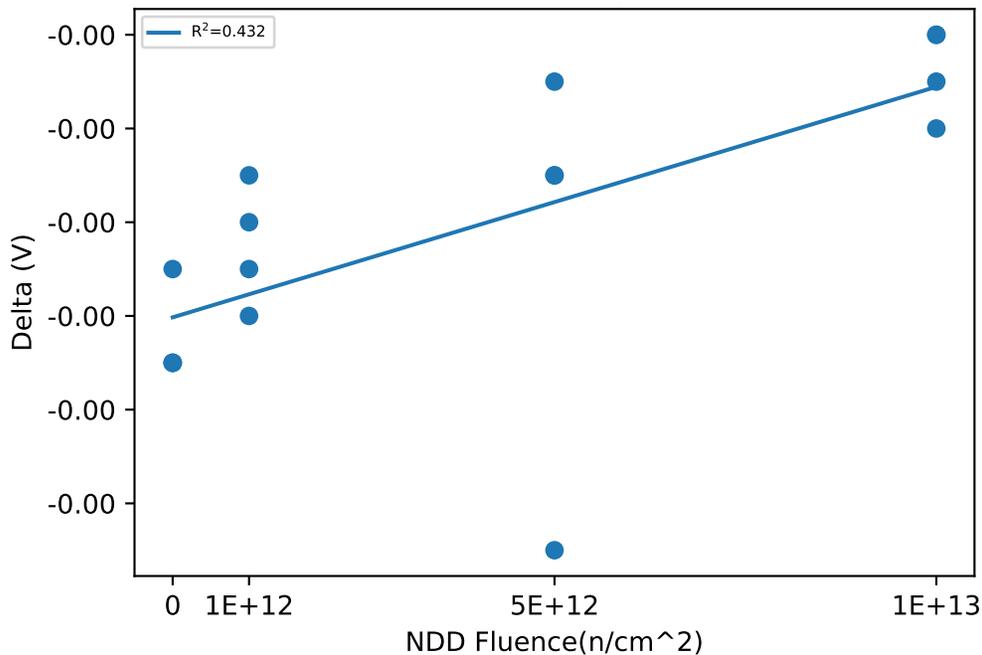
Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1154	0.11568	0.1159	0.000263	0.1138	0.11403	0.1142	0.00020616	-0.0017	-0.00165	-0.0015	0.0001
1e+12	0.1149	0.1152	0.1158	0.00040825	0.1134	0.11375	0.1143	0.0003873	-0.0016	-0.00145	-0.0013	0.0001291
5e+12	0.1154	0.1159	0.1163	0.00042426	0.1142	0.11445	0.1149	0.00031091	-0.0021	-0.00145	-0.0011	0.00044347
1e+13	0.1153	0.1159	0.1168	0.00064807	0.1141	0.11482	0.1157	0.0006702	-0.0012	-0.001075	-0.001	9.5743e-05
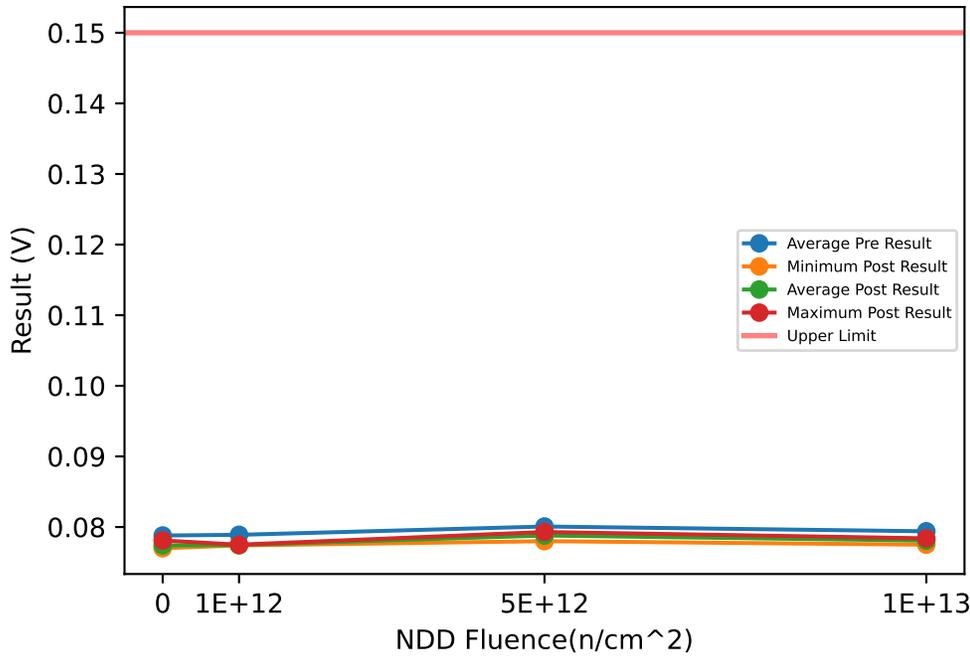
Device Test: 24.7 LEVEL|LOW_LEVEL/OUTL/14/14/0/0/5/500kHz//@OUT_VOL

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 0.15 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.0788	0.0774	-0.0014
2	1e+12	NDD	0.079	0.0775	-0.0015
3	1e+12	NDD	0.079	0.0774	-0.0016
4	1e+12	NDD	0.0788	0.0775	-0.0013
5	5e+12	NDD	0.0804	0.0793	-0.0011
6	5e+12	NDD	0.0803	0.079	-0.0013
7	5e+12	NDD	0.0794	0.078	-0.0014
8	5e+12	NDD	0.0802	0.0789	-0.0013
9	1e+13	NDD	0.0796	0.0783	-0.0013
10	1e+13	NDD	0.0798	0.0784	-0.0014
11	1e+13	NDD	0.0796	0.0781	-0.0015
12	1e+13	NDD	0.0786	0.0775	-0.0011
91	0	CORRELATION	0.0785	0.0772	-0.0013
92	0	CORRELATION	0.0784	0.077	-0.0014
93	0	CORRELATION	0.0789	0.0773	-0.0016
94	0	CORRELATION	0.0794	0.0781	-0.0013
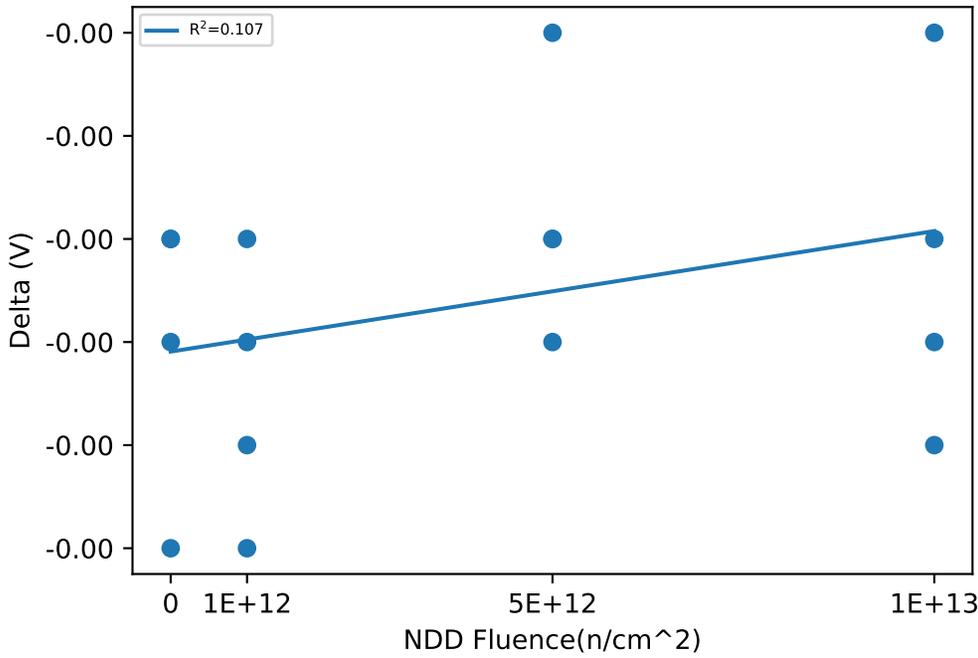
Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0784	0.0788	0.0794	0.00045461	0.077	0.0774	0.0781	0.00048305	-0.0016	-0.0014	-0.0013	0.00014142
1e+12	0.0788	0.0789	0.079	0.00011547	0.0774	0.07745	0.0775	5.7735e-05	-0.0016	-0.00145	-0.0013	0.0001291
5e+12	0.0794	0.080075	0.0804	0.00045735	0.078	0.0788	0.0793	0.00055976	-0.0014	-0.001275	-0.0011	0.00012583
1e+13	0.0786	0.0794	0.0798	0.0005416	0.0775	0.078075	0.0784	0.00040311	-0.0015	-0.001325	-0.0011	0.00017078

Device Test: 24.8 LEVEL|HIGH_LEVEL/OUTH/14/14/0/0/5/500kHz//@OUT_VOH

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 0.25 (V))

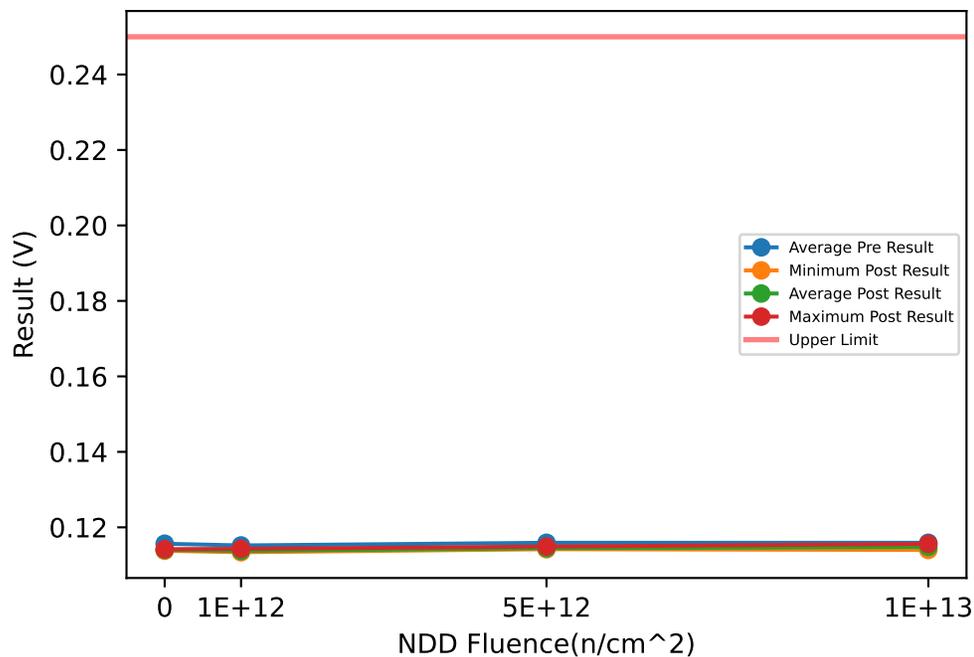| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.115	0.1134	-0.0016
2	1e+12	NDD	0.1151	0.1137	-0.0014
3	1e+12	NDD	0.1149	0.1136	-0.0013
4	1e+12	NDD	0.1158	0.1143	-0.0015
5	5e+12	NDD	0.1158	0.1144	-0.0014
6	5e+12	NDD	0.1162	0.1149	-0.0013
7	5e+12	NDD	0.1154	0.1143	-0.0011
8	5e+12	NDD	0.1162	0.1142	-0.002
9	1e+13	NDD	0.1153	0.114	-0.0013
10	1e+13	NDD	0.1156	0.1146	-0.001
11	1e+13	NDD	0.116	0.115	-0.001
12	1e+13	NDD	0.1167	0.1156	-0.0011
91	0	CORRELATION	0.1159	0.1142	-0.0017
92	0	CORRELATION	0.1155	0.1138	-0.0017
93	0	CORRELATION	0.1154	0.1139	-0.0015
94	0	CORRELATION	0.1158	0.1142	-0.0016
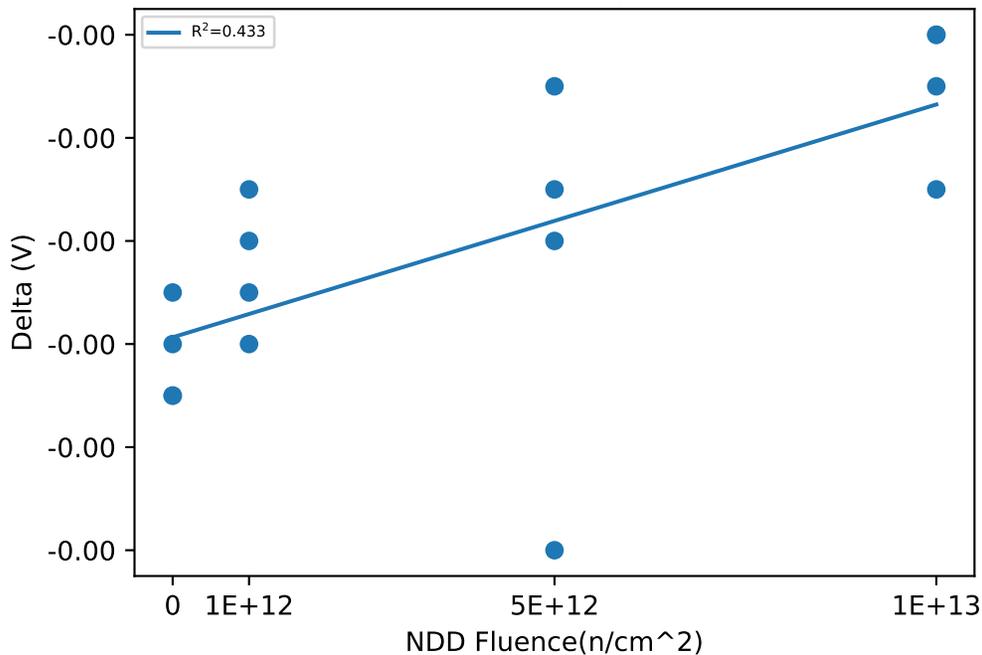
Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1154	0.11565	0.1159	0.00023805	0.1138	0.11403	0.1142	0.00020616	-0.0017	-0.001625	-0.0015	9.5743e-05
1e+12	0.1149	0.1152	0.1158	0.00040825	0.1134	0.11375	0.1143	0.0003873	-0.0016	-0.00145	-0.0013	0.0001291
5e+12	0.1154	0.1159	0.1162	0.00038297	0.1142	0.11445	0.1149	0.00031091	-0.002	-0.00145	-0.0011	0.0003873
1e+13	0.1153	0.1159	0.1167	0.00060553	0.114	0.1148	0.1156	0.0006733	-0.0013	-0.0011	-0.001	0.00014142
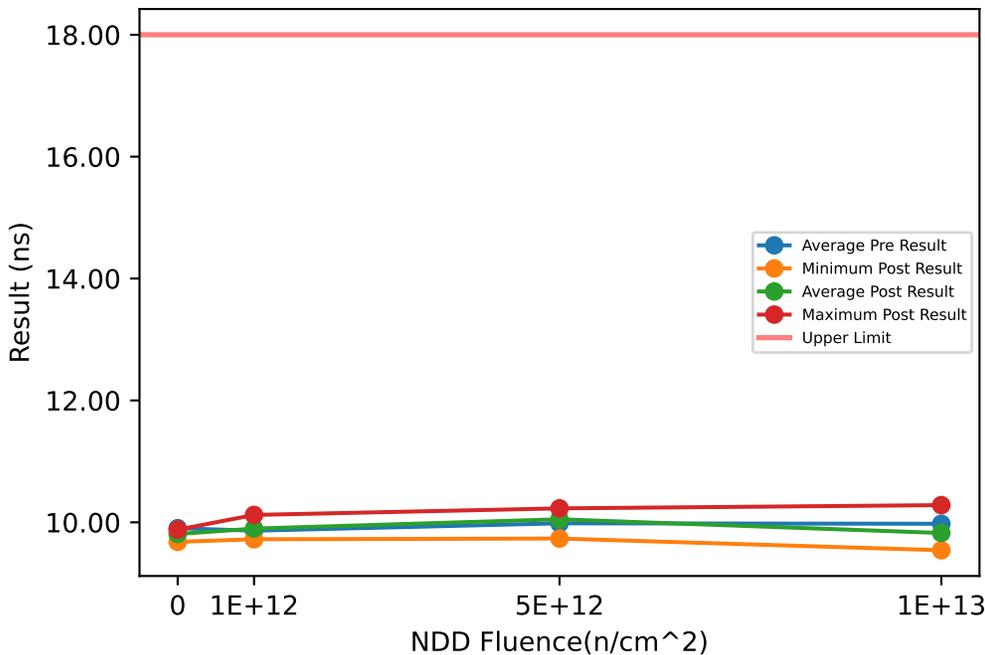
Device Test: 24.9 TIMING|OUT_RISE/OUTH/12/12/0/1000/5/500kHz//@OUT_RISE_12V

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 18.0 (ns))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	10.01	10.121	0.1111
2	1e+12	NDD	9.675	9.722	0.047
3	1e+12	NDD	9.9592	9.9089	-0.0503
4	1e+12	NDD	9.8059	9.8358	0.0299
5	5e+12	NDD	10.186	10.212	0.0257
6	5e+12	NDD	9.8536	10.024	0.1708
7	5e+12	NDD	9.9202	9.7341	-0.1861
8	5e+12	NDD	9.9747	10.229	0.2544
9	1e+13	NDD	10.201	9.5423	-0.6588
10	1e+13	NDD	9.696	9.6879	-0.0081
11	1e+13	NDD	9.9662	9.7879	-0.1783
12	1e+13	NDD	10.042	10.282	0.2398
91	0	CORRELATION	10.156	9.68	-0.4765
92	0	CORRELATION	9.8039	9.8795	0.0756
93	0	CORRELATION	9.8395	9.8381	-0.0014
94	0	CORRELATION	9.8138	9.8362	0.0224
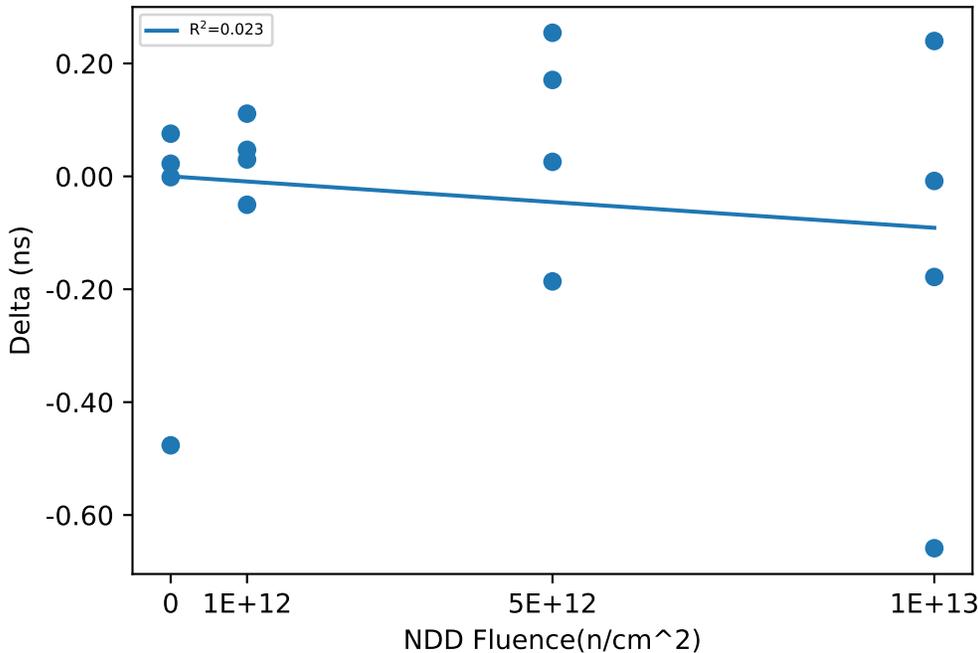
Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.8039	9.9034	10.156	0.16938	9.68	9.8085	9.8795	0.087933	-0.4765	-0.094975	0.0756	0.25638
1e+12	9.675	9.8625	10.01	0.15217	9.722	9.897	10.121	0.16806	-0.0503	0.034425	0.1111	0.066423
5e+12	9.8536	9.9836	10.186	0.14372	9.7341	10.05	10.229	0.22998	-0.1861	0.0662	0.2544	0.19292
1e+13	9.696	9.9764	10.201	0.21099	9.5423	9.825	10.282	0.32091	-0.6588	-0.15135	0.2398	0.37936
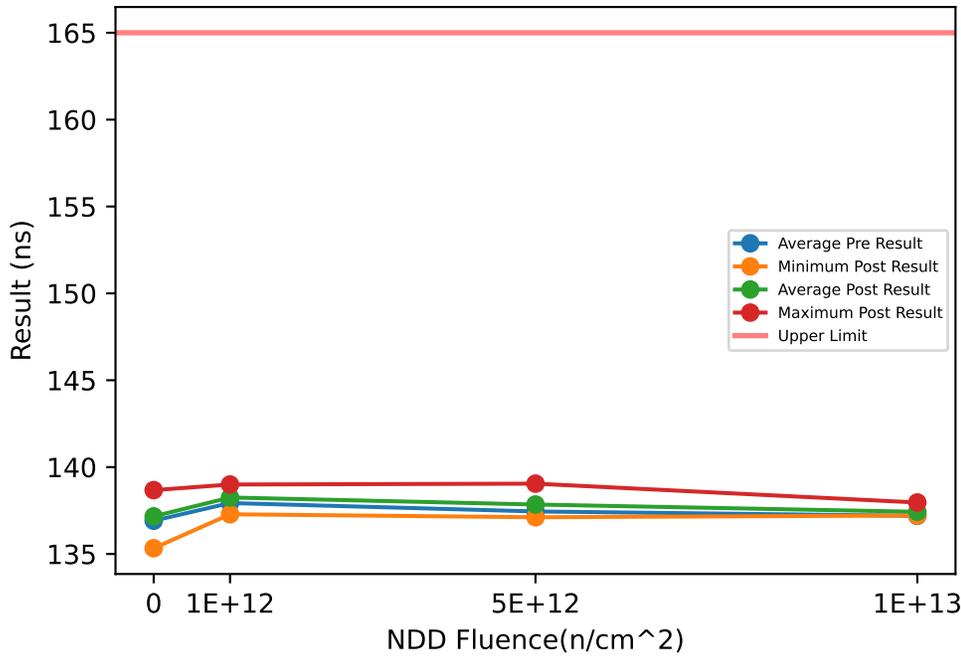
Device Test: 26.3 TIMING|MIN/OUT/12/12/0/0/5/500kHz//@TON_MIN

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 165.0 (ns))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	138.36	138.21	-0.1497
2	1e+12	NDD	137.6	137.29	-0.3104
3	1e+12	NDD	138.13	139	0.865
4	1e+12	NDD	137.64	138.51	0.8683
5	5e+12	NDD	137.04	137.11	0.0756
6	5e+12	NDD	137.59	137.39	-0.1931
7	5e+12	NDD	138.23	139.05	0.8159
8	5e+12	NDD	136.93	137.83	0.8976
9	1e+13	NDD	137.47	137.23	-0.2403
10	1e+13	NDD	137.49	137.3	-0.1945
11	1e+13	NDD	137.45	137.96	0.5095
12	1e+13	NDD	136.36	137.22	0.8586
91	0	CORRELATION	137.21	137.11	-0.106
92	0	CORRELATION	135.65	135.33	-0.3214
93	0	CORRELATION	137.95	138.67	0.7236
94	0	CORRELATION	136.84	137.54	0.7053
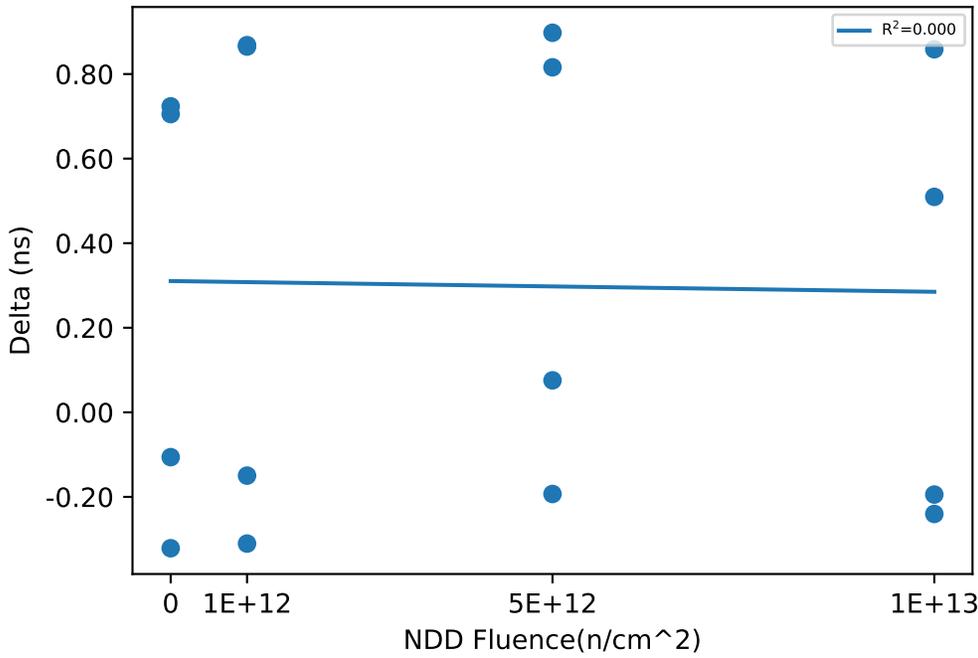
Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	135.65	136.91	137.95	0.95917	135.33	137.16	138.67	1.3889	-0.3214	0.25037	0.7236	0.54309
1e+12	137.6	137.93	138.36	0.37407	137.29	138.25	139	0.72103	-0.3104	0.3183	0.8683	0.63657
5e+12	136.93	137.45	138.23	0.59652	137.11	137.85	139.05	0.85336	-0.1931	0.399	0.8976	0.54086
1e+13	136.36	137.19	137.49	0.55847	137.22	137.43	137.96	0.35877	-0.2403	0.23333	0.8586	0.53994

Device Test: 26.4 TIMING|MIN/OUT/14/14/0/0/5/500kHz//@TON_MIN

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 165.0 (ns))

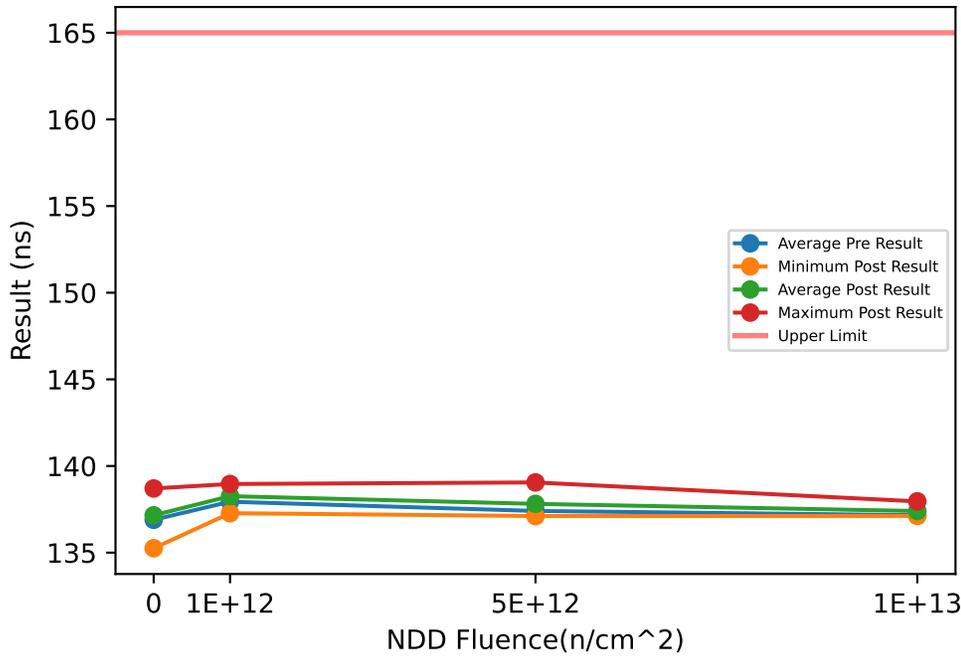| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	138.44	138.28	-0.1618
2	1e+12	NDD	137.59	137.28	-0.3088
3	1e+12	NDD	138.08	138.96	0.8773
4	1e+12	NDD	137.64	138.52	0.8768
5	5e+12	NDD	137.02	137.11	0.092
6	5e+12	NDD	137.55	137.36	-0.1876
7	5e+12	NDD	138.22	139.05	0.8271
8	5e+12	NDD	136.83	137.73	0.9011
9	1e+13	NDD	137.48	137.25	-0.2294
10	1e+13	NDD	137.48	137.28	-0.1978
11	1e+13	NDD	137.44	137.96	0.5199
12	1e+13	NDD	136.25	137.12	0.8715
91	0	CORRELATION	137.2	137.11	-0.0863
92	0	CORRELATION	135.55	135.26	-0.299
93	0	CORRELATION	137.98	138.7	0.7264
94	0	CORRELATION	136.85	137.55	0.7006
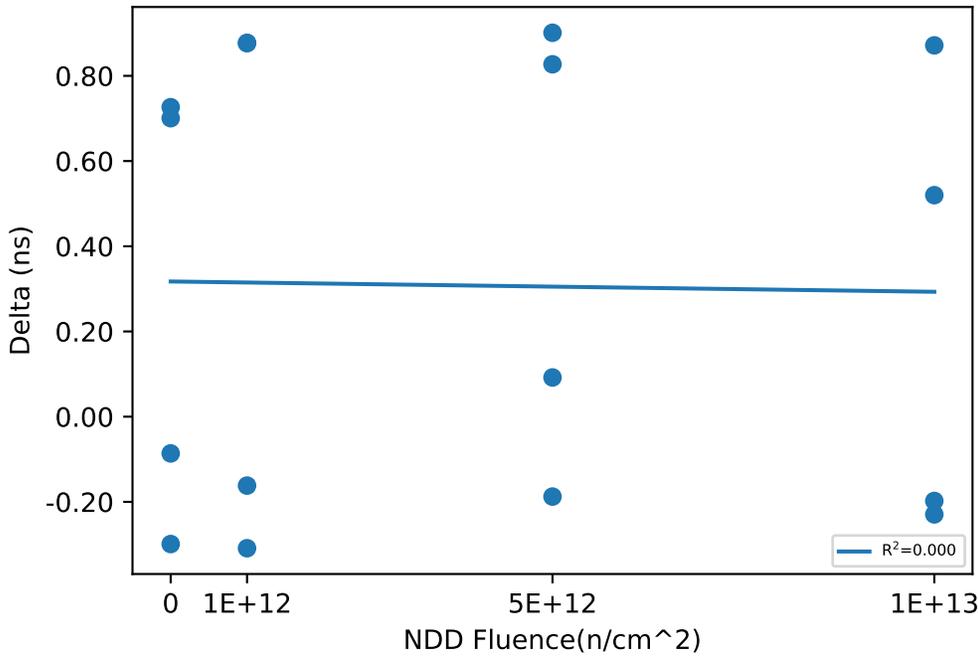
Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	135.55	136.9	137.98	1.0106	135.26	137.16	138.7	1.4337	-0.299	0.26042	0.7264	0.53043
1e+12	137.59	137.94	138.44	0.40161	137.28	138.26	138.96	0.71361	-0.3088	0.32087	0.8773	0.64501
5e+12	136.83	137.41	138.22	0.62319	137.11	137.81	139.05	0.86324	-0.1876	0.40815	0.9011	0.53956
1e+13	136.25	137.16	137.48	0.60971	137.12	137.4	137.96	0.37768	-0.2294	0.24105	0.8715	0.54441

Device Test: 26.5 TIMING|EXT/OUT/14/14/0/0/5/500kHz//@T_OFF_EXTENDER

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 70.0 (ns))

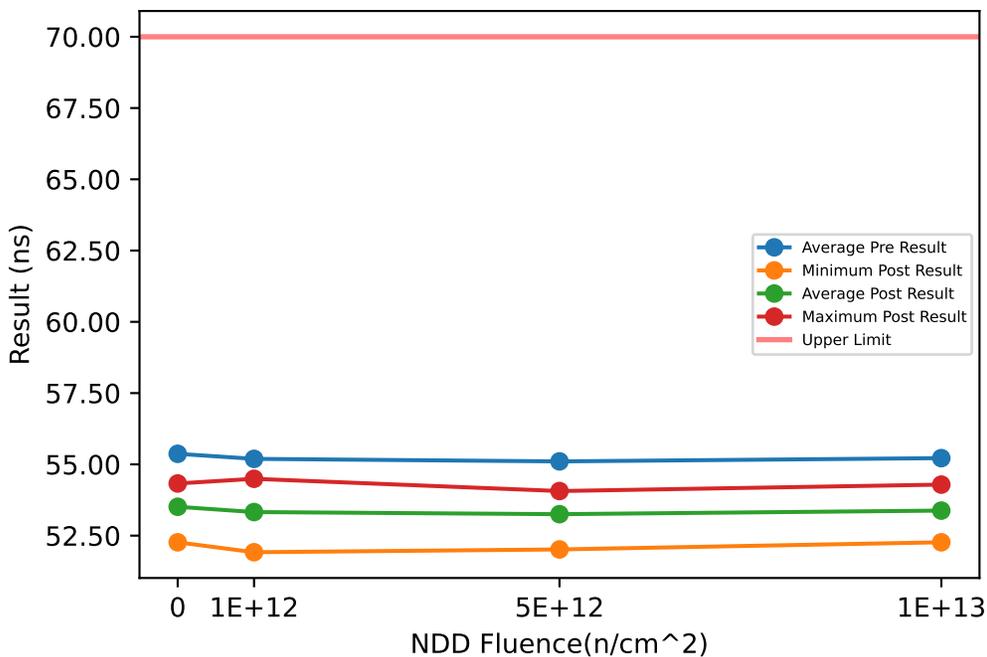| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	55.933	54.494	-1.4395
2	1e+12	NDD	55.47	53.885	-1.5851
3	1e+12	NDD	55.455	53.011	-2.4431
4	1e+12	NDD	53.915	51.918	-1.997
5	5e+12	NDD	55.495	54.064	-1.4312
6	5e+12	NDD	55.369	53.776	-1.5931
7	5e+12	NDD	55.562	53.155	-2.4075
8	5e+12	NDD	53.99	52.016	-1.9741
9	1e+13	NDD	55.706	54.29	-1.4155
10	1e+13	NDD	55.721	54.253	-1.4677
11	1e+13	NDD	55.168	52.704	-2.4638
12	1e+13	NDD	54.281	52.267	-2.0139
91	0	CORRELATION	55.787	54.33	-1.4576
92	0	CORRELATION	55.301	53.672	-1.6297
93	0	CORRELATION	56.183	53.783	-2.4
94	0	CORRELATION	54.21	52.266	-1.9437
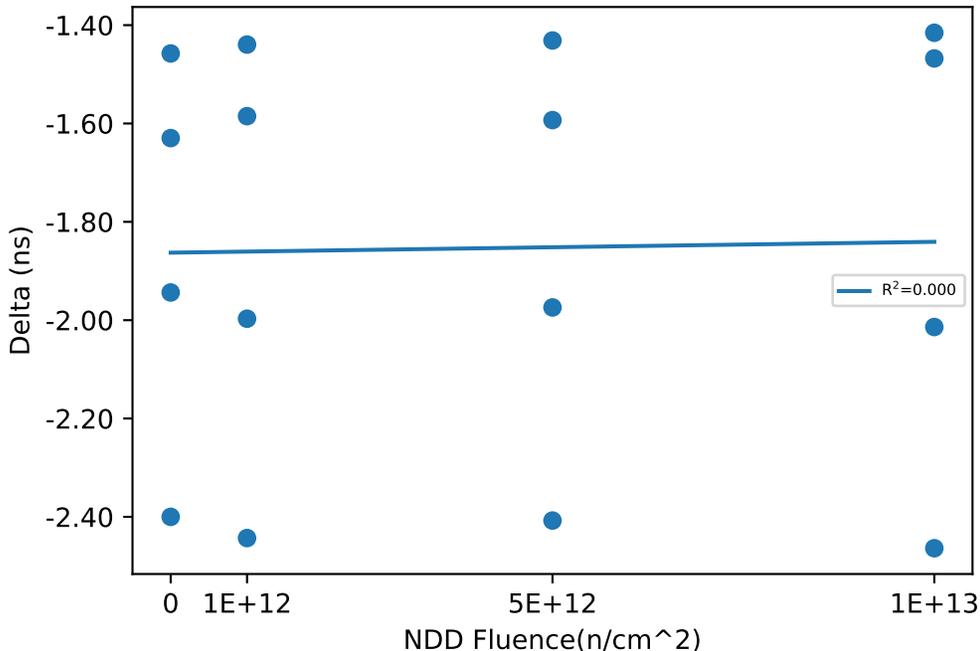
Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	54.21	55.37	56.183	0.85349	52.266	53.513	54.33	0.87935	-2.4	-1.8577	-1.4576	0.41374
1e+12	53.915	55.193	55.933	0.88052	51.918	53.327	54.494	1.1191	-2.4431	-1.8662	-1.4395	0.4513
5e+12	53.99	55.104	55.562	0.747	52.016	53.253	54.064	0.90758	-2.4075	-1.8515	-1.4312	0.43497
1e+13	54.281	55.219	55.721	0.67596	52.267	53.379	54.29	1.0465	-2.4638	-1.8402	-1.4155	0.49604

Device Test: 26.7 TIMING|MIN/OUT/8/8/0/0/5/500kHz//@TON_MIN

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 165.0 (ns))

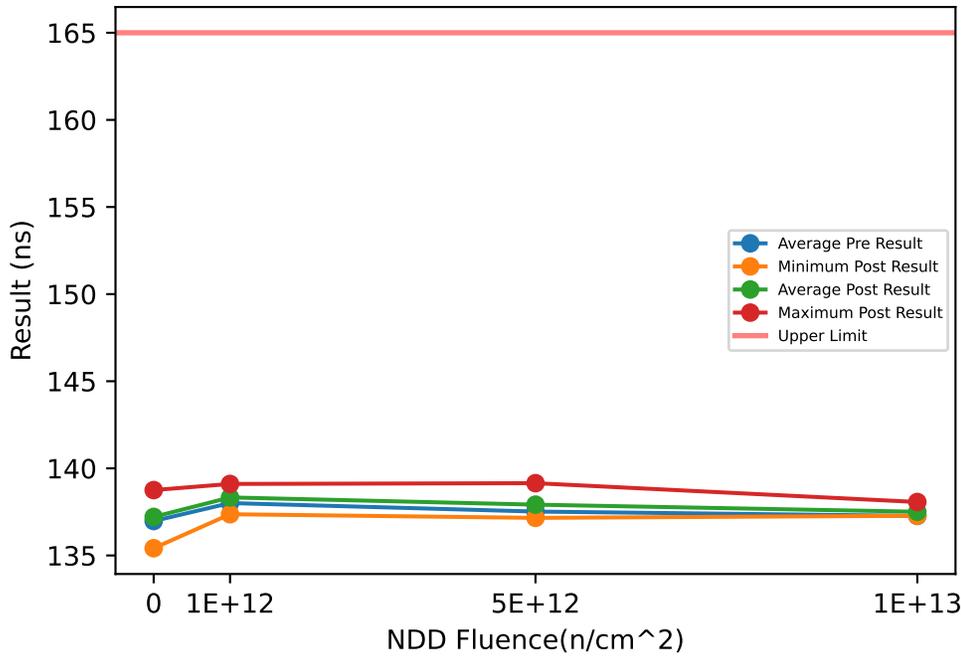| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	138.44	138.31	-0.1362
2	1e+12	NDD	137.67	137.37	-0.3073
3	1e+12	NDD	138.27	139.1	0.8352
4	1e+12	NDD	137.65	138.54	0.8978
5	5e+12	NDD	137.09	137.16	0.0722
6	5e+12	NDD	137.69	137.49	-0.2003
7	5e+12	NDD	138.34	139.15	0.8055
8	5e+12	NDD	136.96	137.87	0.908
9	1e+13	NDD	137.54	137.28	-0.2615
10	1e+13	NDD	137.57	137.39	-0.1835
11	1e+13	NDD	137.56	138.07	0.5128
12	1e+13	NDD	136.42	137.3	0.8831
91	0	CORRELATION	137.26	137.14	-0.1259
92	0	CORRELATION	135.76	135.42	-0.3448
93	0	CORRELATION	138.05	138.75	0.7041
94	0	CORRELATION	136.84	137.54	0.7078
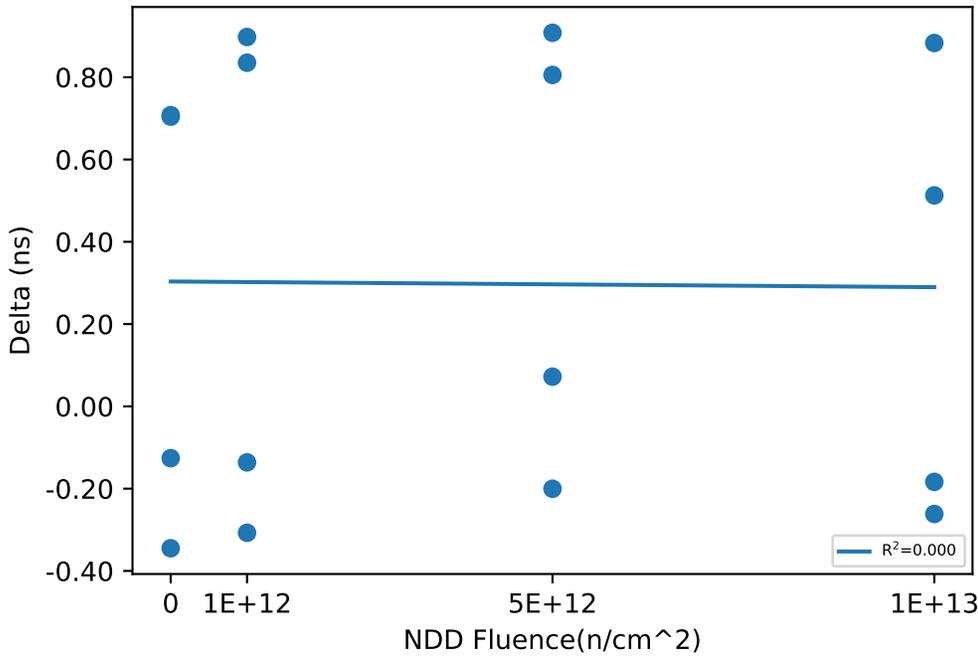
Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	135.76	136.98	138.05	0.95381	135.42	137.21	138.75	1.3802	-0.3448	0.2353	0.7078	0.55076
1e+12	137.65	138.01	138.44	0.40817	137.37	138.33	139.1	0.72468	-0.3073	0.32238	0.8978	0.63269
5e+12	136.96	137.52	138.34	0.63352	137.16	137.92	139.15	0.8722	-0.2003	0.39635	0.908	0.54475
1e+13	136.42	137.27	137.57	0.56736	137.28	137.51	138.07	0.37541	-0.2615	0.23772	0.8831	0.55342

# Device Test: 26.8 TIMING|EXT/OUT/8/8/0/0/5/500kHz//@T_OFF_EXTENDER
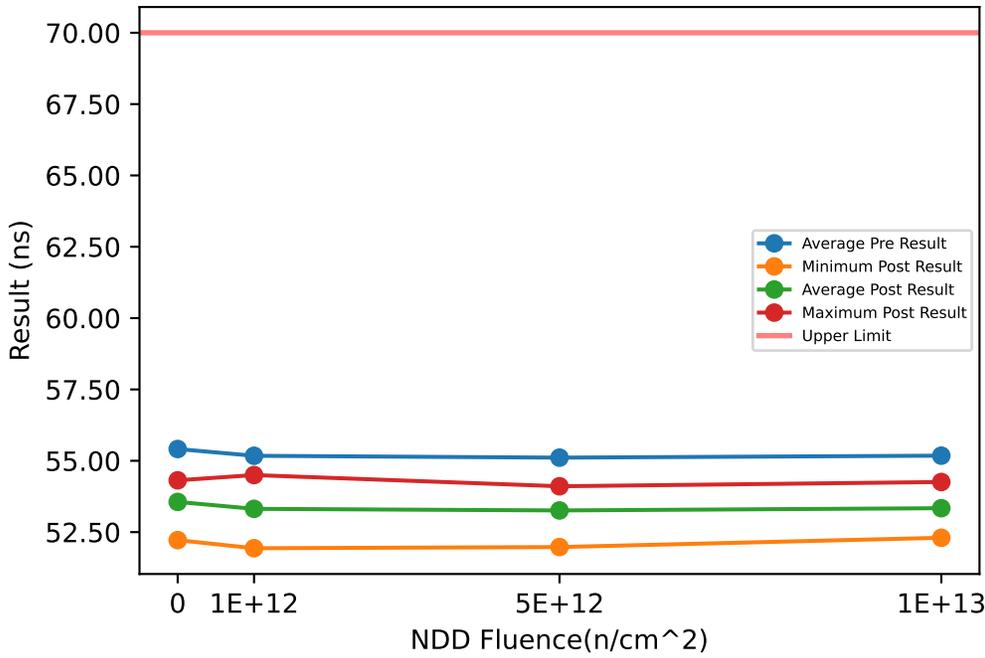
NDD vs Result Stats

Test Results (Upper Limit = 70.0 (ns))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	55.919	54.5	-1.4199
2	1e+12	NDD	55.441	53.879	-1.5625
3	1e+12	NDD	55.417	52.949	-2.4687
4	1e+12	NDD	53.922	51.936	-1.9866
5	5e+12	NDD	55.56	54.107	-1.4533
6	5e+12	NDD	55.438	53.848	-1.5903
7	5e+12	NDD	55.492	53.108	-2.385
8	5e+12	NDD	53.949	51.977	-1.9722
9	1e+13	NDD	55.661	54.256	-1.4047
10	1e+13	NDD	55.578	54.134	-1.4448
11	1e+13	NDD	55.118	52.66	-2.4582
12	1e+13	NDD	54.359	52.302	-2.057
91	0	CORRELATION	55.799	54.315	-1.4837
92	0	CORRELATION	55.366	53.752	-1.6134
93	0	CORRELATION	56.276	53.945	-2.3308
94	0	CORRELATION	54.208	52.219	-1.9886

## NDD vs Post - Pre Exposure Delta
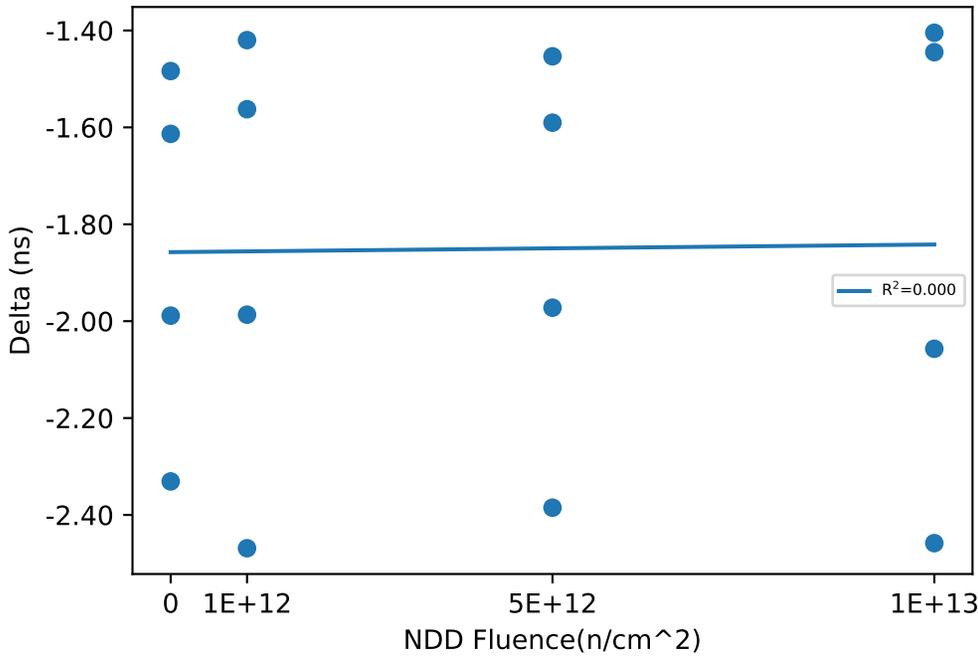
Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	54.208	55.412	56.276	0.88474	52.219	53.558	54.315	0.9225	-2.3308	-1.8541	-1.4837	0.38317
1e+12	53.922	55.175	55.919	0.86669	51.936	53.316	54.5	1.1193	-2.4687	-1.8594	-1.4199	0.47214
5e+12	53.949	55.11	55.56	0.77573	51.977	53.26	54.107	0.95457	-2.385	-1.8502	-1.4533	0.41872
1e+13	54.359	55.179	55.661	0.59651	52.302	53.338	54.256	1.0014	-2.4582	-1.8412	-1.4047	0.50824

Device Test: 27.10 LEVEL|WRST_MAX/OUT/14/14/0/0/5/100kHz//@MAX_DCL_100

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 100.0 (%))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	100	100	0
2	1e+12	NDD	100	100	0
3	1e+12	NDD	100	100	0
4	1e+12	NDD	100	100	0
5	5e+12	NDD	100	100	0
6	5e+12	NDD	100	100	0
7	5e+12	NDD	100	100	0
8	5e+12	NDD	100	100	0
9	1e+13	NDD	100	100	0
10	1e+13	NDD	100	100	0
11	1e+13	NDD	100	100	0
12	1e+13	NDD	100	100	0
91	0	CORRELATION	100	100	0
92	0	CORRELATION	100	100	0
93	0	CORRELATION	100	100	0
94	0	CORRELATION	100	100	0

Test Statistics (%)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	100	100	100	0	100	100	100	0	0	0	0	0
1e+12	100	100	100	0	100	100	100	0	0	0	0	0
5e+12	100	100	100	0	100	100	100	0	0	0	0	0
1e+13	100	100	100	0	100	100	100	0	0	0	0	0

Device Test: 27.11 LEVEL|WRST_MAX/OUT/12/12/0/0/5/200kHz//@MAX_DCL_100

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 100.0 (%))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	100	100	0
2	1e+12	NDD	100	100	0
3	1e+12	NDD	100	100	0
4	1e+12	NDD	100	100	0
5	5e+12	NDD	100	100	0
6	5e+12	NDD	100	100	0
7	5e+12	NDD	100	100	0
8	5e+12	NDD	100	100	0
9	1e+13	NDD	100	100	0
10	1e+13	NDD	100	100	0
11	1e+13	NDD	100	100	0
12	1e+13	NDD	100	100	0
91	0	CORRELATION	100	100	0
92	0	CORRELATION	100	100	0
93	0	CORRELATION	100	100	0
94	0	CORRELATION	100	100	0

Test Statistics (%)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	100	100	100	0	100	100	100	0	0	0	0	0
1e+12	100	100	100	0	100	100	100	0	0	0	0	0
5e+12	100	100	100	0	100	100	100	0	0	0	0	0
1e+13	100	100	100	0	100	100	100	0	0	0	0	0

Device Test: 27.12 LEVEL|WRST_MAX/OUT/14/14/0/0/5/200kHz//@MAX_DCL_100

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 100.0 (%))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	100	100	0
2	1e+12	NDD	100	100	0
3	1e+12	NDD	100	100	0
4	1e+12	NDD	100	100	0
5	5e+12	NDD	100	100	0
6	5e+12	NDD	100	100	0
7	5e+12	NDD	100	100	0
8	5e+12	NDD	100	100	0
9	1e+13	NDD	100	100	0
10	1e+13	NDD	100	100	0
11	1e+13	NDD	100	100	0
12	1e+13	NDD	100	100	0
91	0	CORRELATION	100	100	0
92	0	CORRELATION	100	100	0
93	0	CORRELATION	100	100	0
94	0	CORRELATION	100	100	0

Test Statistics (%)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	100	100	100	0	100	100	100	0	0	0	0	0
1e+12	100	100	100	0	100	100	100	0	0	0	0	0
5e+12	100	100	100	0	100	100	100	0	0	0	0	0
1e+13	100	100	100	0	100	100	100	0	0	0	0	0

Device Test: 27.13 LEVEL|WRST_MAX/OUT/12/12/0/0/5/500kHz//@MAX_DCL_100

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 100.0 (%))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	100	100	0
2	1e+12	NDD	100	100	0
3	1e+12	NDD	100	100	0
4	1e+12	NDD	100	100	0
5	5e+12	NDD	100	100	0
6	5e+12	NDD	100	100	0
7	5e+12	NDD	100	100	0
8	5e+12	NDD	100	100	0
9	1e+13	NDD	100	100	0
10	1e+13	NDD	100	100	0
11	1e+13	NDD	100	100	0
12	1e+13	NDD	100	100	0
91	0	CORRELATION	100	100	0
92	0	CORRELATION	100	100	0
93	0	CORRELATION	100	100	0
94	0	CORRELATION	100	100	0

Test Statistics (%)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	100	100	100	0	100	100	100	0	0	0	0	0
1e+12	100	100	100	0	100	100	100	0	0	0	0	0
5e+12	100	100	100	0	100	100	100	0	0	0	0	0
1e+13	100	100	100	0	100	100	100	0	0	0	0	0

Device Test: 27.14 LEVEL|WRST_MAX/OUT/14/14/0/0/5/500kHz//@MAX_DCL_100

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 100.0 (%))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	100	100	0
2	1e+12	NDD	100	100	0
3	1e+12	NDD	100	100	0
4	1e+12	NDD	100	100	0
5	5e+12	NDD	100	100	0
6	5e+12	NDD	100	100	0
7	5e+12	NDD	100	100	0
8	5e+12	NDD	100	100	0
9	1e+13	NDD	100	100	0
10	1e+13	NDD	100	100	0
11	1e+13	NDD	100	100	0
12	1e+13	NDD	100	100	0
91	0	CORRELATION	100	100	0
92	0	CORRELATION	100	100	0
93	0	CORRELATION	100	100	0
94	0	CORRELATION	100	100	0

Test Statistics (%)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	100	100	100	0	100	100	100	0	0	0	0	0
1e+12	100	100	100	0	100	100	100	0	0	0	0	0
5e+12	100	100	100	0	100	100	100	0	0	0	0	0
1e+13	100	100	100	0	100	100	100	0	0	0	0	0

Device Test: 27.15 LEVEL|DCL/OUT/8/8/0/0/5/100kHz//@MAX_DCL_100

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 100.0 (%))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	100	100	0
2	1e+12	NDD	100	100	0
3	1e+12	NDD	100	100	0
4	1e+12	NDD	100	100	0
5	5e+12	NDD	100	100	0
6	5e+12	NDD	100	100	0
7	5e+12	NDD	100	100	0
8	5e+12	NDD	100	100	0
9	1e+13	NDD	100	100	0
10	1e+13	NDD	100	100	0
11	1e+13	NDD	100	100	0
12	1e+13	NDD	100	100	0
91	0	CORRELATION	100	100	0
92	0	CORRELATION	100	100	0
93	0	CORRELATION	100	100	0
94	0	CORRELATION	100	100	0

Test Statistics (%)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	100	100	100	0	100	100	100	0	0	0	0	0
1e+12	100	100	100	0	100	100	100	0	0	0	0	0
5e+12	100	100	100	0	100	100	100	0	0	0	0	0
1e+13	100	100	100	0	100	100	100	0	0	0	0	0

Device Test: 27.16 LEVEL|DCL/OUT/8/8/0/0/5/200kHz//@MAX_DCL_100

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 100.0 (%))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	100	100	0
2	1e+12	NDD	100	100	0
3	1e+12	NDD	100	100	0
4	1e+12	NDD	100	100	0
5	5e+12	NDD	100	100	0
6	5e+12	NDD	100	100	0
7	5e+12	NDD	100	100	0
8	5e+12	NDD	100	100	0
9	1e+13	NDD	100	100	0
10	1e+13	NDD	100	100	0
11	1e+13	NDD	100	100	0
12	1e+13	NDD	100	100	0
91	0	CORRELATION	100	100	0
92	0	CORRELATION	100	100	0
93	0	CORRELATION	100	100	0
94	0	CORRELATION	100	100	0

Test Statistics (%)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	100	100	100	0	100	100	100	0	0	0	0	0
1e+12	100	100	100	0	100	100	100	0	0	0	0	0
5e+12	100	100	100	0	100	100	100	0	0	0	0	0
1e+13	100	100	100	0	100	100	100	0	0	0	0	0

Device Test: 27.17 LEVEL|DCL/OUT/8/8/0/0/5/500kHz//@MAX_DCL_100

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 100.0 (%))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	100	100	0
2	1e+12	NDD	100	100	0
3	1e+12	NDD	100	100	0
4	1e+12	NDD	100	100	0
5	5e+12	NDD	100	100	0
6	5e+12	NDD	100	100	0
7	5e+12	NDD	100	100	0
8	5e+12	NDD	100	100	0
9	1e+13	NDD	100	100	0
10	1e+13	NDD	100	100	0
11	1e+13	NDD	100	100	0
12	1e+13	NDD	100	100	0
91	0	CORRELATION	100	100	0
92	0	CORRELATION	100	100	0
93	0	CORRELATION	100	100	0
94	0	CORRELATION	100	100	0

Test Statistics (%)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	100	100	100	0	100	100	100	0	0	0	0	0
1e+12	100	100	100	0	100	100	100	0	0	0	0	0
5e+12	100	100	100	0	100	100	100	0	0	0	0	0
1e+13	100	100	100	0	100	100	100	0	0	0	0	0

Device Test: 27.18 LEVEL|WRST_MAX/OUT/8/8/0/0/5/100kHz//@MAX_DCL_100

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 100.0 (%))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	100	100	0
2	1e+12	NDD	100	100	0
3	1e+12	NDD	100	100	0
4	1e+12	NDD	100	100	0
5	5e+12	NDD	100	100	0
6	5e+12	NDD	100	100	0
7	5e+12	NDD	100	100	0
8	5e+12	NDD	100	100	0
9	1e+13	NDD	100	100	0
10	1e+13	NDD	100	100	0
11	1e+13	NDD	100	100	0
12	1e+13	NDD	100	100	0
91	0	CORRELATION	100	100	0
92	0	CORRELATION	100	100	0
93	0	CORRELATION	100	100	0
94	0	CORRELATION	100	100	0

Test Statistics (%)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	100	100	100	0	100	100	100	0	0	0	0	0
1e+12	100	100	100	0	100	100	100	0	0	0	0	0
5e+12	100	100	100	0	100	100	100	0	0	0	0	0
1e+13	100	100	100	0	100	100	100	0	0	0	0	0

Device Test: 27.19 LEVEL|WRST_MAX/OUT/8/8/0/0/5/200kHz//@MAX_DCL_100

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 100.0 (%))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	100	100	0
2	1e+12	NDD	100	100	0
3	1e+12	NDD	100	100	0
4	1e+12	NDD	100	100	0
5	5e+12	NDD	100	100	0
6	5e+12	NDD	100	100	0
7	5e+12	NDD	100	100	0
8	5e+12	NDD	100	100	0
9	1e+13	NDD	100	100	0
10	1e+13	NDD	100	100	0
11	1e+13	NDD	100	100	0
12	1e+13	NDD	100	100	0
91	0	CORRELATION	100	100	0
92	0	CORRELATION	100	100	0
93	0	CORRELATION	100	100	0
94	0	CORRELATION	100	100	0

Test Statistics (%)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	100	100	100	0	100	100	100	0	0	0	0	0
1e+12	100	100	100	0	100	100	100	0	0	0	0	0
5e+12	100	100	100	0	100	100	100	0	0	0	0	0
1e+13	100	100	100	0	100	100	100	0	0	0	0	0

Device Test: 27.20 LEVEL|WRST_MAX/OUT/8/8/0/0/5/500kHz//@MAX_DCL_100

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 100.0 (%))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	100	100	0
2	1e+12	NDD	100	100	0
3	1e+12	NDD	100	100	0
4	1e+12	NDD	100	100	0
5	5e+12	NDD	100	100	0
6	5e+12	NDD	100	100	0
7	5e+12	NDD	100	100	0
8	5e+12	NDD	100	100	0
9	1e+13	NDD	100	100	0
10	1e+13	NDD	100	100	0
11	1e+13	NDD	100	100	0
12	1e+13	NDD	100	100	0
91	0	CORRELATION	100	100	0
92	0	CORRELATION	100	100	0
93	0	CORRELATION	100	100	0
94	0	CORRELATION	100	100	0

Test Statistics (%)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	100	100	100	0	100	100	100	0	0	0	0	0
1e+12	100	100	100	0	100	100	100	0	0	0	0	0
5e+12	100	100	100	0	100	100	100	0	0	0	0	0
1e+13	100	100	100	0	100	100	100	0	0	0	0	0

Device Test: 27.3 LEVEL|DCL/OUT/12/12/0/0/5/100kHz//@MAX_DCL_100

NDD vs Result Stats

Legend:
- Average Pre Result
- Minimum Post Result
- Average Post Result
- Maximum Post Result
- Upper Limit

NDD vs Post - Pre Exposure Delta

- R^2=1.000

Test Results (Upper Limit = 100.0 (%))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	100	100	0
2	1e+12	NDD	100	100	0
3	1e+12	NDD	100	100	0
4	1e+12	NDD	100	100	0
5	5e+12	NDD	100	100	0
6	5e+12	NDD	100	100	0
7	5e+12	NDD	100	100	0
8	5e+12	NDD	100	100	0
9	1e+13	NDD	100	100	0
10	1e+13	NDD	100	100	0
11	1e+13	NDD	100	100	0
12	1e+13	NDD	100	100	0
91	0	CORRELATION	100	100	0
92	0	CORRELATION	100	100	0
93	0	CORRELATION	100	100	0
94	0	CORRELATION	100	100	0

Test Statistics (%)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	100	100	100	0	100	100	100	0	0	0	0	0
1e+12	100	100	100	0	100	100	100	0	0	0	0	0
5e+12	100	100	100	0	100	100	100	0	0	0	0	0
1e+13	100	100	100	0	100	100	100	0	0	0	0	0

Device Test: 27.4 LEVEL|DCL/OUT/14/14/0/0/5/100kHz//@MAX_DCL_100

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 100.0 (%))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	100	100	0
2	1e+12	NDD	100	100	0
3	1e+12	NDD	100	100	0
4	1e+12	NDD	100	100	0
5	5e+12	NDD	100	100	0
6	5e+12	NDD	100	100	0
7	5e+12	NDD	100	100	0
8	5e+12	NDD	100	100	0
9	1e+13	NDD	100	100	0
10	1e+13	NDD	100	100	0
11	1e+13	NDD	100	100	0
12	1e+13	NDD	100	100	0
91	0	CORRELATION	100	100	0
92	0	CORRELATION	100	100	0
93	0	CORRELATION	100	100	0
94	0	CORRELATION	100	100	0

Test Statistics (%)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	100	100	100	0	100	100	100	0	0	0	0	0
1e+12	100	100	100	0	100	100	100	0	0	0	0	0
5e+12	100	100	100	0	100	100	100	0	0	0	0	0
1e+13	100	100	100	0	100	100	100	0	0	0	0	0

Device Test: 27.5 LEVEL|DCL/OUT/12/12/0/0/5/200kHz//@MAX_DCL_100

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 100.0 (%))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	100	100	0
2	1e+12	NDD	100	100	0
3	1e+12	NDD	100	100	0
4	1e+12	NDD	100	100	0
5	5e+12	NDD	100	100	0
6	5e+12	NDD	100	100	0
7	5e+12	NDD	100	100	0
8	5e+12	NDD	100	100	0
9	1e+13	NDD	100	100	0
10	1e+13	NDD	100	100	0
11	1e+13	NDD	100	100	0
12	1e+13	NDD	100	100	0
91	0	CORRELATION	100	100	0
92	0	CORRELATION	100	100	0
93	0	CORRELATION	100	100	0
94	0	CORRELATION	100	100	0

Test Statistics (%)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	100	100	100	0	100	100	100	0	0	0	0	0
1e+12	100	100	100	0	100	100	100	0	0	0	0	0
5e+12	100	100	100	0	100	100	100	0	0	0	0	0
1e+13	100	100	100	0	100	100	100	0	0	0	0	0

Device Test: 27.6 LEVEL|DCL/OUT/14/14/0/0/5/200kHz//@MAX_DCL_100

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 100.0 (%))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	100	100	0
2	1e+12	NDD	100	100	0
3	1e+12	NDD	100	100	0
4	1e+12	NDD	100	100	0
5	5e+12	NDD	100	100	0
6	5e+12	NDD	100	100	0
7	5e+12	NDD	100	100	0
8	5e+12	NDD	100	100	0
9	1e+13	NDD	100	100	0
10	1e+13	NDD	100	100	0
11	1e+13	NDD	100	100	0
12	1e+13	NDD	100	100	0
91	0	CORRELATION	100	100	0
92	0	CORRELATION	100	100	0
93	0	CORRELATION	100	100	0
94	0	CORRELATION	100	100	0

Test Statistics (%)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	100	100	100	0	100	100	100	0	0	0	0	0
1e+12	100	100	100	0	100	100	100	0	0	0	0	0
5e+12	100	100	100	0	100	100	100	0	0	0	0	0
1e+13	100	100	100	0	100	100	100	0	0	0	0	0

Device Test: 27.7 LEVEL|DCL/OUT/12/12/0/0/5/500kHz//@MAX_DCL_100

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 100.0 (%))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	100	100	0
2	1e+12	NDD	100	100	0
3	1e+12	NDD	100	100	0
4	1e+12	NDD	100	100	0
5	5e+12	NDD	100	100	0
6	5e+12	NDD	100	100	0
7	5e+12	NDD	100	100	0
8	5e+12	NDD	100	100	0
9	1e+13	NDD	100	100	0
10	1e+13	NDD	100	100	0
11	1e+13	NDD	100	100	0
12	1e+13	NDD	100	100	0
91	0	CORRELATION	100	100	0
92	0	CORRELATION	100	100	0
93	0	CORRELATION	100	100	0
94	0	CORRELATION	100	100	0

Test Statistics (%)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	100	100	100	0	100	100	100	0	0	0	0	0
1e+12	100	100	100	0	100	100	100	0	0	0	0	0
5e+12	100	100	100	0	100	100	100	0	0	0	0	0
1e+13	100	100	100	0	100	100	100	0	0	0	0	0

Device Test: 27.8 LEVEL|DCL/OUT/14/14/0/0/5/500kHz//@MAX_DCL_100

NDD vs Result Stats

Legend:
- Average Pre Result
- Minimum Post Result
- Average Post Result
- Maximum Post Result
- Upper Limit

Y-axis: Result (%) — 104, 102, 100, 98.00, 96.00
X-axis: NDD Fluence(n/cm^2) — 0, 1E+12, 5E+12, 1E+13

NDD vs Post - Pre Exposure Delta

$R^2=1.000$

Y-axis: Delta (%) — 0.04, 0.02, 0.00, -0.02, -0.04
X-axis: NDD Fluence(n/cm^2) — 0, 1E+12, 5E+12, 1E+13

Test Results (Upper Limit = 100.0 (%))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	100	100	0
2	1e+12	NDD	100	100	0
3	1e+12	NDD	100	100	0
4	1e+12	NDD	100	100	0
5	5e+12	NDD	100	100	0
6	5e+12	NDD	100	100	0
7	5e+12	NDD	100	100	0
8	5e+12	NDD	100	100	0
9	1e+13	NDD	100	100	0
10	1e+13	NDD	100	100	0
11	1e+13	NDD	100	100	0
12	1e+13	NDD	100	100	0
91	0	CORRELATION	100	100	0
92	0	CORRELATION	100	100	0
93	0	CORRELATION	100	100	0
94	0	CORRELATION	100	100	0

Test Statistics (%)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	100	100	100	0	100	100	100	0	0	0	0	0
1e+12	100	100	100	0	100	100	100	0	0	0	0	0
5e+12	100	100	100	0	100	100	100	0	0	0	0	0
1e+13	100	100	100	0	100	100	100	0	0	0	0	0

Device Test: 27.9 LEVEL|WRST_MAX/OUT/12/12/0/0/5/100kHz//@MAX_DCL_100

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 100.0 (%))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	100	100	0
2	1e+12	NDD	100	100	0
3	1e+12	NDD	100	100	0
4	1e+12	NDD	100	100	0
5	5e+12	NDD	100	100	0
6	5e+12	NDD	100	100	0
7	5e+12	NDD	100	100	0
8	5e+12	NDD	100	100	0
9	1e+13	NDD	100	100	0
10	1e+13	NDD	100	100	0
11	1e+13	NDD	100	100	0
12	1e+13	NDD	100	100	0
91	0	CORRELATION	100	100	0
92	0	CORRELATION	100	100	0
93	0	CORRELATION	100	100	0
94	0	CORRELATION	100	100	0

Test Statistics (%)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	100	100	100	0	100	100	100	0	0	0	0	0
1e+12	100	100	100	0	100	100	100	0	0	0	0	0
5e+12	100	100	100	0	100	100	100	0	0	0	0	0
1e+13	100	100	100	0	100	100	100	0	0	0	0	0

Device Test: 28.10 VOLTAGE|OC/CS/14/14/0/0/5/500kHz//@V_CS_ILIM_OC

NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 0.96, Upper Limit = 1.04 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.9929	0.9928	-0.0001
2	1e+12	NDD	0.9993	0.997	-0.0023
3	1e+12	NDD	1.0022	1.0033	0.0011
4	1e+12	NDD	0.9974	0.996	-0.0014
5	5e+12	NDD	0.9918	0.9883	-0.0035
6	5e+12	NDD	0.993	0.9896	-0.0034
7	5e+12	NDD	0.9899	0.9868	-0.0031
8	5e+12	NDD	0.9899	0.9881	-0.0018
9	1e+13	NDD	0.9992	0.9929	-0.0063
10	1e+13	NDD	0.993	0.9896	-0.0034
11	1e+13	NDD	0.9946	0.9898	-0.0048
12	1e+13	NDD	0.9824	0.9794	-0.003
91	0	CORRELATION	0.9988	0.9988	0
92	0	CORRELATION	0.9945	0.993	-0.0015
93	0	CORRELATION	0.9915	0.9913	-0.0002
94	0	CORRELATION	0.9916	0.9911	-0.0005
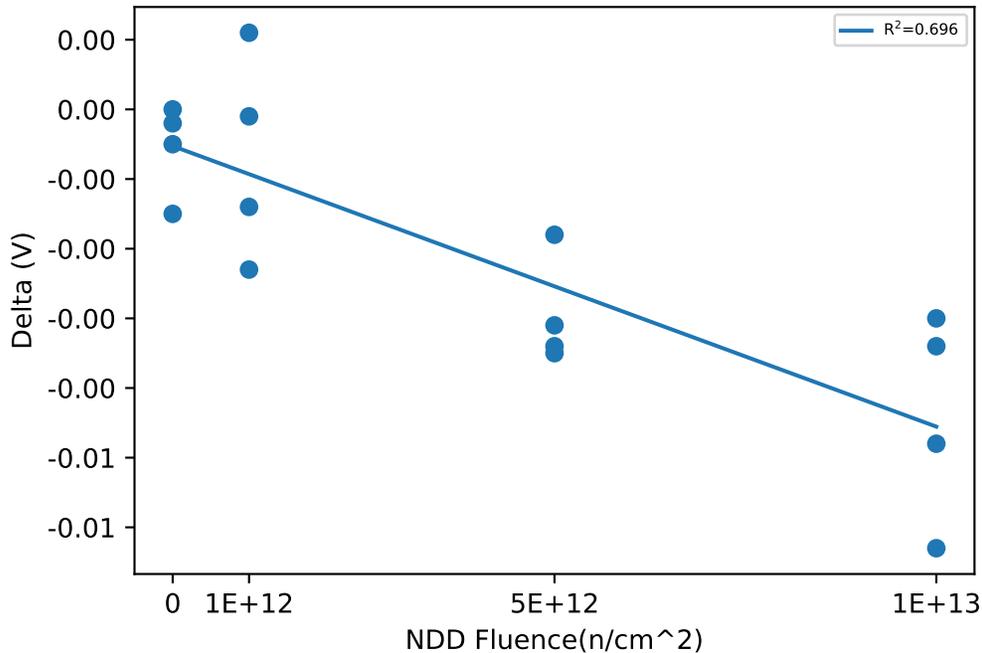
Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9915	0.9941	0.9988	0.0034283	0.9911	0.99355	0.9988	0.0036023	-0.0015	-0.00055	0	0.00066583
1e+12	0.9929	0.99795	1.0022	0.0039026	0.9928	0.99728	1.0033	0.004398	-0.0023	-0.000675	0.0011	0.0014886
5e+12	0.9899	0.99115	0.993	0.0015242	0.9868	0.9882	0.9896	0.001146	-0.0035	-0.00295	-0.0018	0.00078528
1e+13	0.9824	0.9923	0.9992	0.007104	0.9794	0.98793	0.9929	0.0058807	-0.0063	-0.004375	-0.003	0.0014975
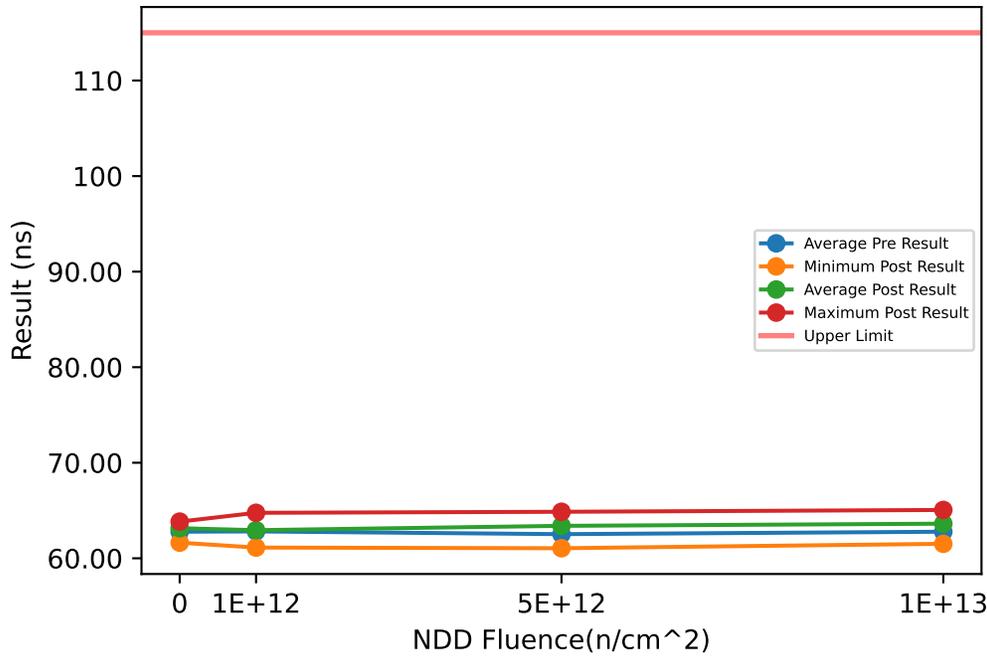
Device Test: 28.11 TIMING|DELAY/CS/12/12/0/0/5/100kHz//@CS_ILIM_DELAY

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 115.0 (ns))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	62.275	61.713	-0.5614
2	1e+12	NDD	61.041	61.123	0.0814
3	1e+12	NDD	65.023	64.76	-0.263
4	1e+12	NDD	62.913	64.171	1.2573
5	5e+12	NDD	62.058	63.164	1.1059
6	5e+12	NDD	60.912	61.053	0.1418
7	5e+12	NDD	63.945	64.498	0.553
8	5e+12	NDD	63.189	64.867	1.678
9	1e+13	NDD	62.559	63.478	0.9191
10	1e+13	NDD	60.803	61.517	0.7139
11	1e+13	NDD	64.132	65.057	0.9256
12	1e+13	NDD	63.629	64.439	0.8099
91	0	CORRELATION	63.379	63.471	0.0917
92	0	CORRELATION	61.596	61.637	0.0411
93	0	CORRELATION	63.309	63.838	0.5289
94	0	CORRELATION	62.847	63.644	0.7969
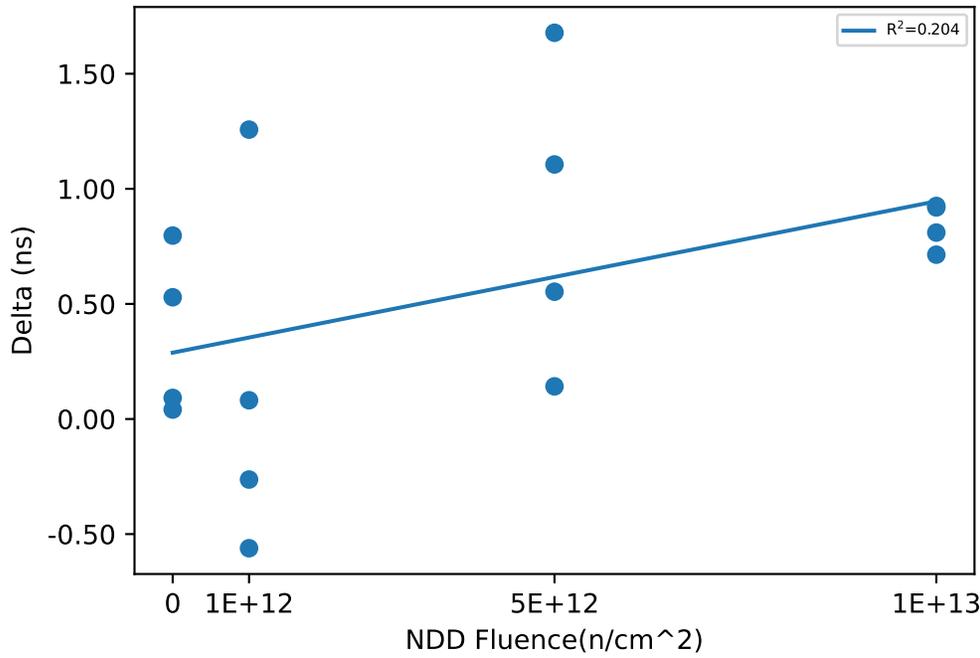
Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	61.596	62.783	63.379	0.82564	61.637	63.147	63.838	1.0181	0.0411	0.36465	0.7969	0.36194
1e+12	61.041	62.813	65.023	1.6658	61.123	62.942	64.76	1.7922	-0.5614	0.12857	1.2573	0.797
5e+12	60.912	62.526	63.945	1.3266	61.053	63.396	64.867	1.7244	0.1418	0.86968	1.678	0.66815
1e+13	60.803	62.781	64.132	1.4724	61.517	63.623	65.057	1.5469	0.7139	0.84213	0.9256	0.10062
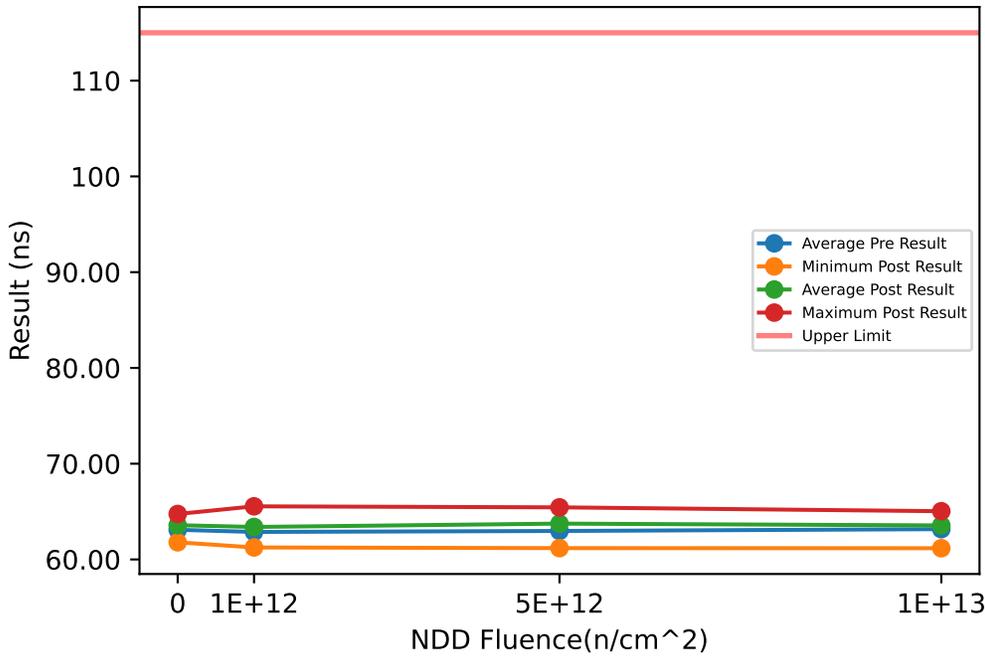
Device Test: 28.12 TIMING|DELAY/CS/14/14/0/0/5/100kHz//@CS_ILIM_DELAY

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 115.0 (ns))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	61.464	62.597	1.1335
2	1e+12	NDD	61.839	61.252	-0.5871
3	1e+12	NDD	65.107	65.547	0.4395
4	1e+12	NDD	63.082	64.172	1.0908
5	5e+12	NDD	62.209	63.273	1.0641
6	5e+12	NDD	61.924	61.183	-0.7413
7	5e+12	NDD	63.575	65.441	1.865
8	5e+12	NDD	64.191	65.07	0.8792
9	1e+13	NDD	63.424	63.073	-0.3508
10	1e+13	NDD	61.132	61.172	0.0397
11	1e+13	NDD	64.334	64.928	0.5939
12	1e+13	NDD	63.768	65.038	1.2708
91	0	CORRELATION	63.794	64.507	0.7129
92	0	CORRELATION	61.792	61.792	-0.0008
93	0	CORRELATION	63.763	64.748	0.9842
94	0	CORRELATION	63.042	63.255	0.2134
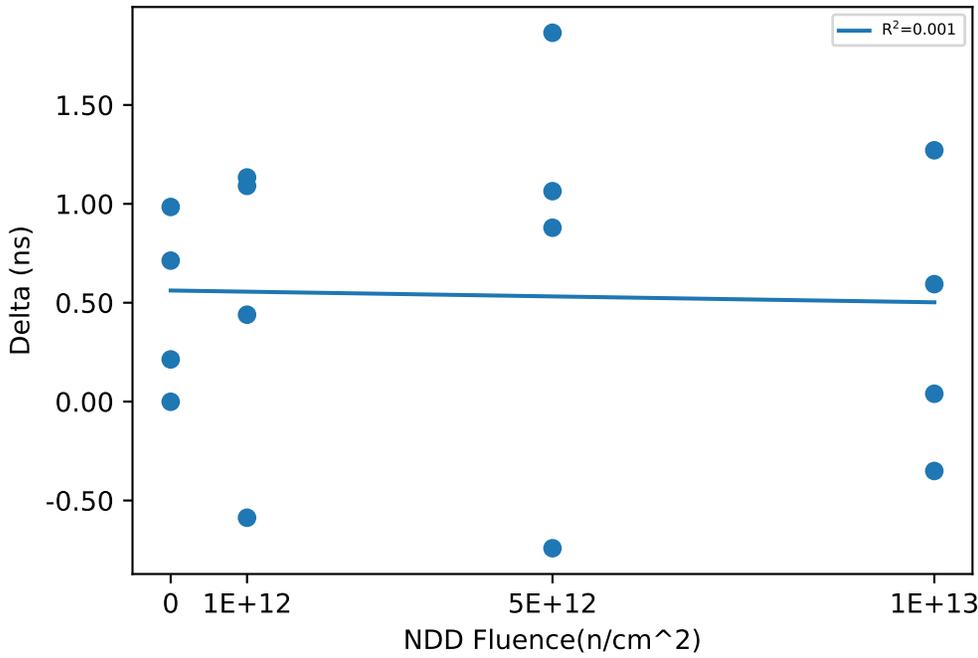
Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	61.792	63.098	63.794	0.93718	61.792	63.575	64.748	1.3572	-0.0008	0.47743	0.9842	0.45118
1e+12	61.464	62.873	65.107	1.6421	61.252	63.392	65.547	1.8675	-0.5871	0.51917	1.1335	0.80298
5e+12	61.924	62.975	64.191	1.0847	61.183	63.742	65.441	1.9508	-0.7413	0.76675	1.865	1.0926
1e+13	61.132	63.165	64.334	1.4057	61.172	63.553	65.038	1.8253	-0.3508	0.3884	1.2708	0.70448
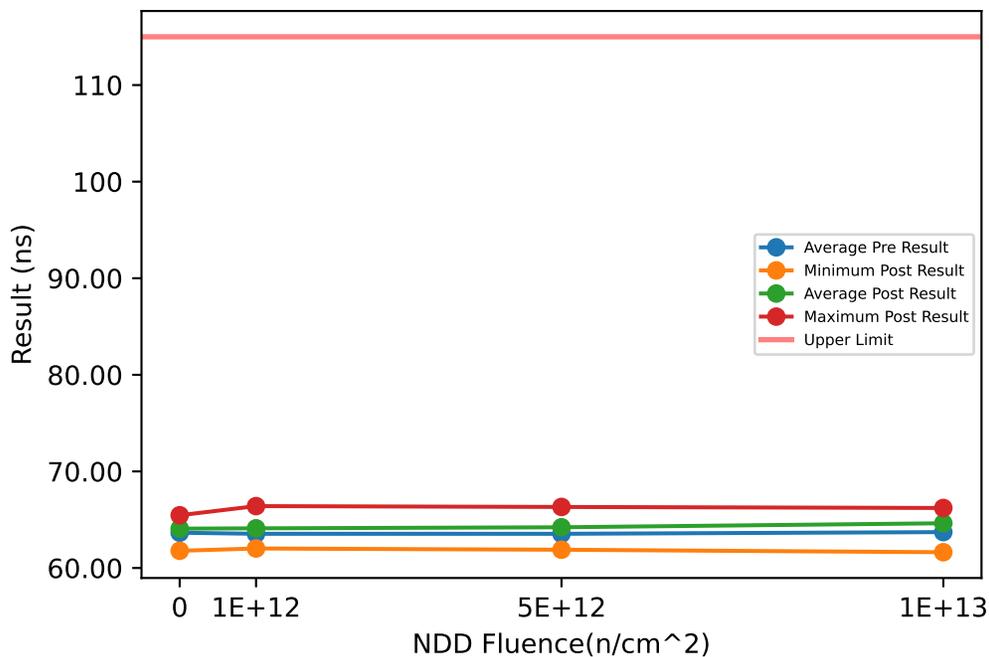
Device Test: 28.13 TIMING|DELAY/CS/12/12/0/1000/5/100kHz//@CS_ILIM_DELAY

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 115.0 (ns))

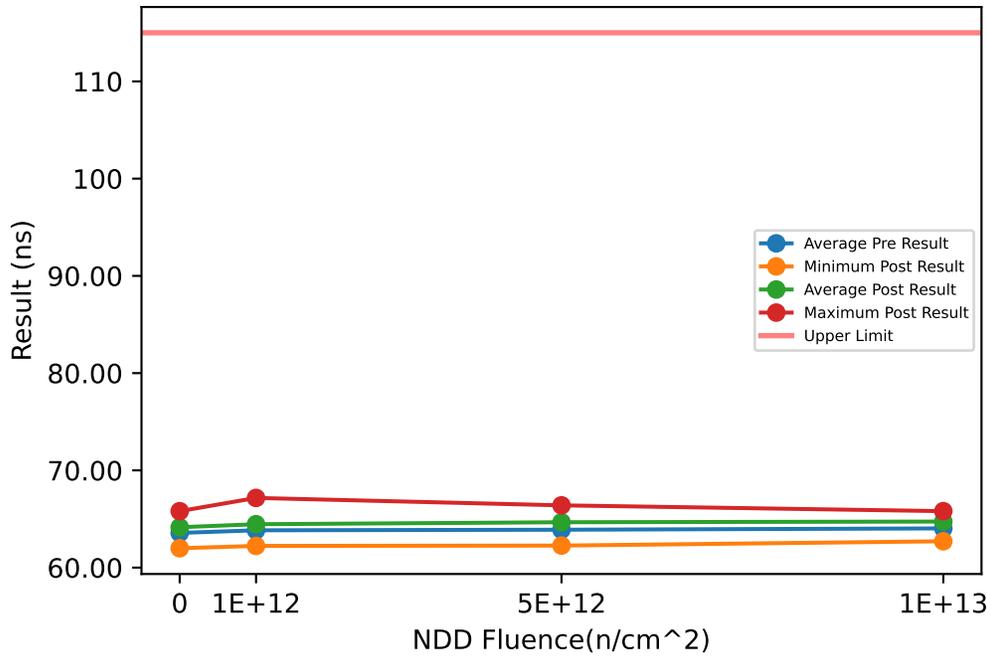| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	62.855	63.11	0.2552
2	1e+12	NDD	62.012	62.02	0.0079
3	1e+12	NDD	65.679	66.407	0.7277
4	1e+12	NDD	63.62	64.889	1.2694
5	5e+12	NDD	63.405	63.286	-0.1193
6	5e+12	NDD	61.851	61.891	0.0397
7	5e+12	NDD	64.827	66.32	1.4924
8	5e+12	NDD	64.078	65.364	1.2864
9	1e+13	NDD	63.452	64.569	1.1171
10	1e+13	NDD	62.288	61.633	-0.6553
11	1e+13	NDD	64.185	66.213	2.0282
12	1e+13	NDD	64.941	66.112	1.1709
91	0	CORRELATION	64.453	64.52	0.0675
92	0	CORRELATION	62.584	61.783	-0.8014
93	0	CORRELATION	63.957	65.46	1.5027
94	0	CORRELATION	63.62	64.529	0.9095
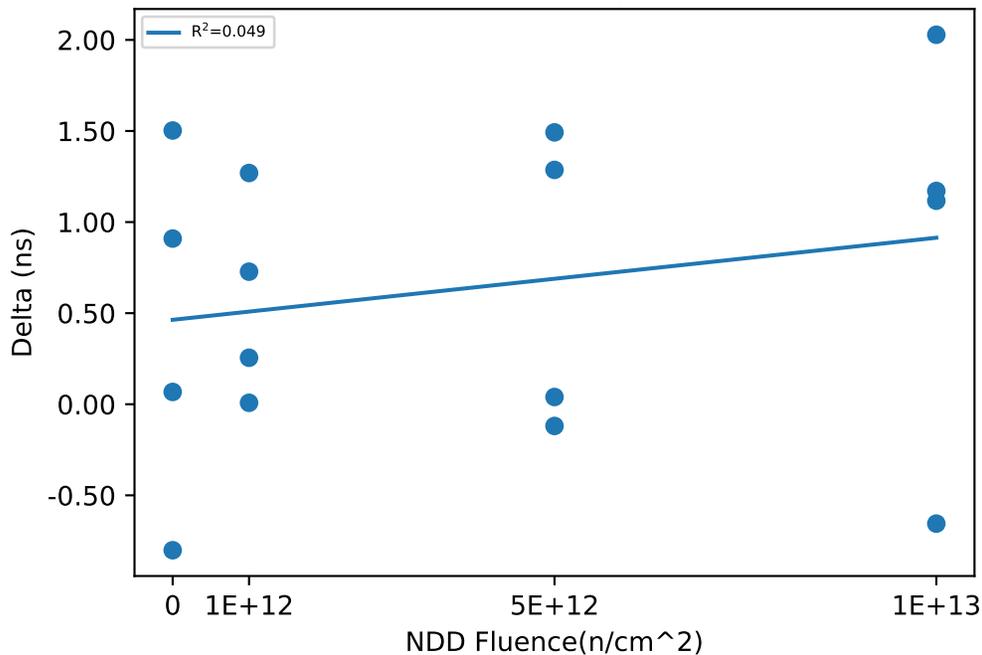
Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	62.584	63.653	64.453	0.79067	61.783	64.073	65.46	1.5892	-0.8014	0.41958	1.5027	1.0046
1e+12	62.012	63.541	65.679	1.5692	62.02	64.106	66.407	1.9367	0.0079	0.56505	1.2694	0.55647
5e+12	61.851	63.54	64.827	1.2672	61.891	64.215	66.32	2.0014	-0.1193	0.6748	1.4924	0.83196
1e+13	62.288	63.716	64.941	1.1298	61.633	64.632	66.213	2.1363	-0.6553	0.91522	2.0282	1.1271

# Device Test: 28.14 TIMING|DELAY/CS/14/14/0/1000/5/100kHz//@CS_ILIM_DELAY

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 115.0 (ns))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	63.037	62.954	-0.0837
2	1e+12	NDD	62.798	62.232	-0.5666
3	1e+12	NDD	65.095	67.165	2.0699
4	1e+12	NDD	64.414	65.497	1.083
5	5e+12	NDD	63.19	63.961	0.7702
6	5e+12	NDD	62.894	62.264	-0.6299
7	5e+12	NDD	64.395	66.402	2.007
8	5e+12	NDD	65.103	66.031	0.9283
9	1e+13	NDD	63.736	64.706	0.9705
10	1e+13	NDD	62.645	62.709	0.0637
11	1e+13	NDD	64.48	65.806	1.3266
12	1e+13	NDD	65.268	65.719	0.4507
91	0	CORRELATION	64.878	64.785	-0.0938
92	0	CORRELATION	62.347	61.993	-0.354
93	0	CORRELATION	63.716	65.804	2.0883
94	0	CORRELATION	63.329	64.021	0.6923
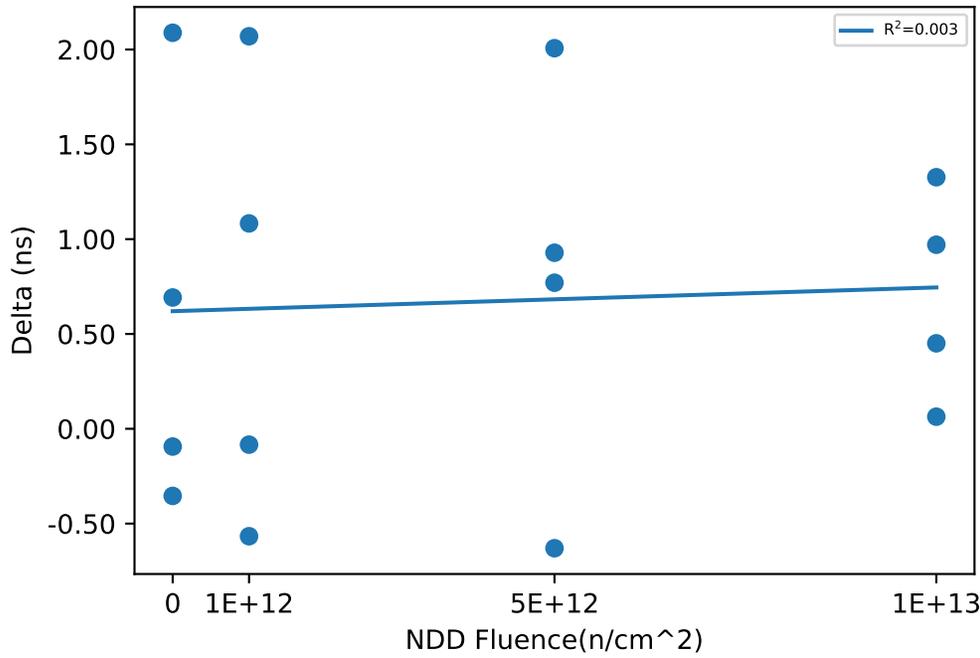
Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	62.347	63.567	64.878	1.0468	61.993	64.151	65.804	1.6133	-0.354	0.5832	2.0883	1.0976
1e+12	62.798	63.836	65.095	1.1005	62.232	64.462	67.165	2.2822	-0.5666	0.62565	2.0699	1.186
5e+12	62.894	63.896	65.103	1.0341	62.264	64.665	66.402	1.9274	-0.6299	0.7689	2.007	1.0824
1e+13	62.645	64.032	65.268	1.1166	62.709	64.735	65.806	1.4402	0.0637	0.70288	1.3266	0.55761
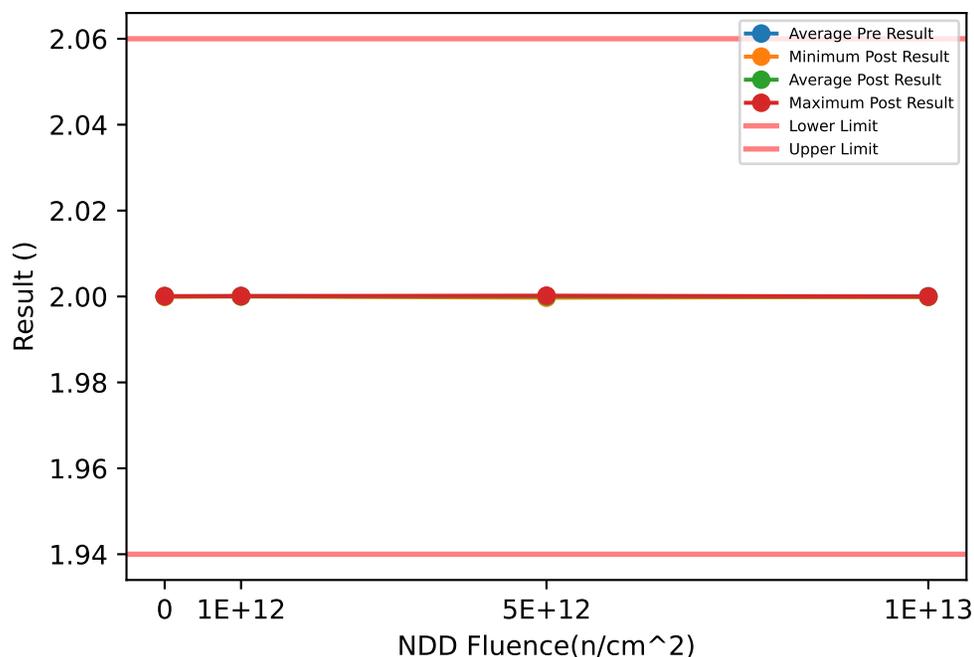
Device Test: 28.15 LEVEL|RATIO/CS/8/8/0/0/5/500kHz//@C_CS_R

## NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 1.94, Upper Limit = 2.06 ())

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	2	2	0
2	1e+12	NDD	2	2	0
3	1e+12	NDD	2.0001	2	-0.0001
4	1e+12	NDD	2.0003	2.0001	-0.0002
5	5e+12	NDD	2	2	0
6	5e+12	NDD	1.9999	2.0002	0.0003
7	5e+12	NDD	1.9999	2.0001	0.0002
8	5e+12	NDD	2.0001	1.9997	-0.0004
9	1e+13	NDD	2	2	0
10	1e+13	NDD	2.0001	2	-0.0001
11	1e+13	NDD	2	1.9999	-0.0001
12	1e+13	NDD	2.0001	1.9999	-0.0002
91	0	CORRELATION	1.9999	2.0001	0.0002
92	0	CORRELATION	2.0001	2.0001	0
93	0	CORRELATION	2.0001	2.0001	0
94	0	CORRELATION	2	1.9999	-0.0001
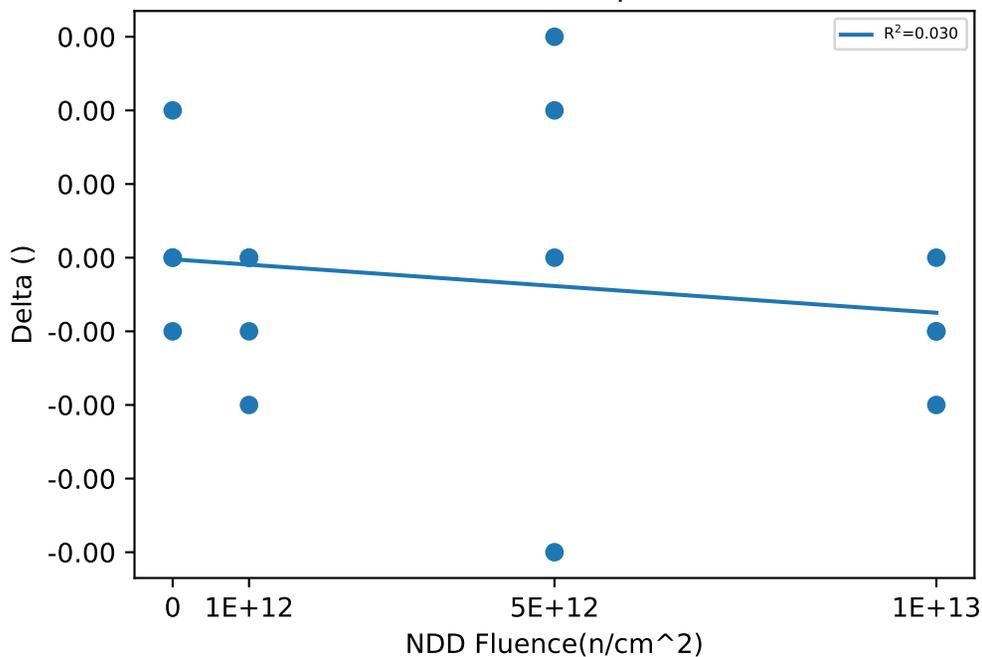
Test Statistics ()

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.9999	2	2.0001	9.5743e-05	1.9999	2.0001	2.0001	0.0001	-0.0001	2.5e-05	0.0002	0.00012583
1e+12	2	2.0001	2.0003	0.00014142	2	2	2.0001	5e-05	-0.0002	-7.5e-05	0	9.5743e-05
5e+12	1.9999	2	2.0001	9.5743e-05	1.9997	2	2.0002	0.00021602	-0.0004	2.5e-05	0.0003	0.00030957
1e+13	2	2	2.0001	5.7735e-05	1.9999	2	2	5.7735e-05	-0.0002	-0.0001	0	8.165e-05
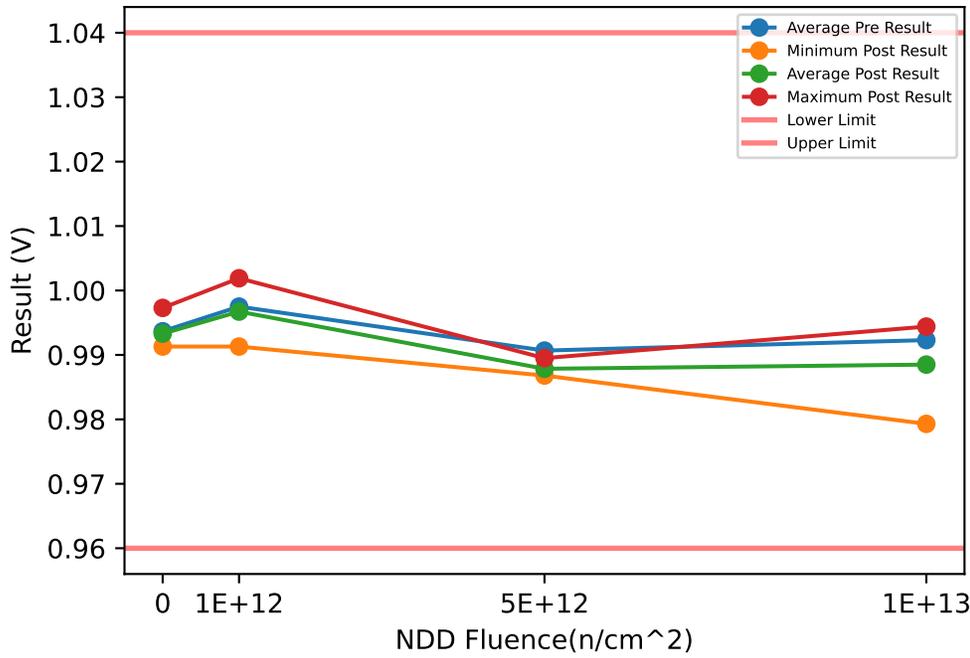
Device Test: 28.17 VOLTAGE|OC/CS/8/8/0/0/5/100kHz//@V_CS_ILIM_OC

NDD vs Result Stats

Legend:
- Average Pre Result
- Minimum Post Result
- Average Post Result
- Maximum Post Result
- Lower Limit
- Upper Limit

NDD vs Post - Pre Exposure Delta

R² = 0.736

Test Results (Lower Limit = 0.96, Upper Limit = 1.04 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.9931	0.9913	-0.0018
2	1e+12	NDD	0.9974	0.9977	0.0003
3	1e+12	NDD	1.0022	1.0019	-0.0003
4	1e+12	NDD	0.9973	0.996	-0.0013
5	5e+12	NDD	0.9914	0.9883	-0.0031
6	5e+12	NDD	0.993	0.9895	-0.0035
7	5e+12	NDD	0.9884	0.9868	-0.0016
8	5e+12	NDD	0.9899	0.9868	-0.0031
9	1e+13	NDD	0.9991	0.9944	-0.0047
10	1e+13	NDD	0.9932	0.9903	-0.0029
11	1e+13	NDD	0.9946	0.99	-0.0046
12	1e+13	NDD	0.9823	0.9793	-0.003
91	0	CORRELATION	0.9988	0.9973	-0.0015
92	0	CORRELATION	0.9928	0.993	0.0002
93	0	CORRELATION	0.9915	0.9913	-0.0002
94	0	CORRELATION	0.9916	0.9916	0
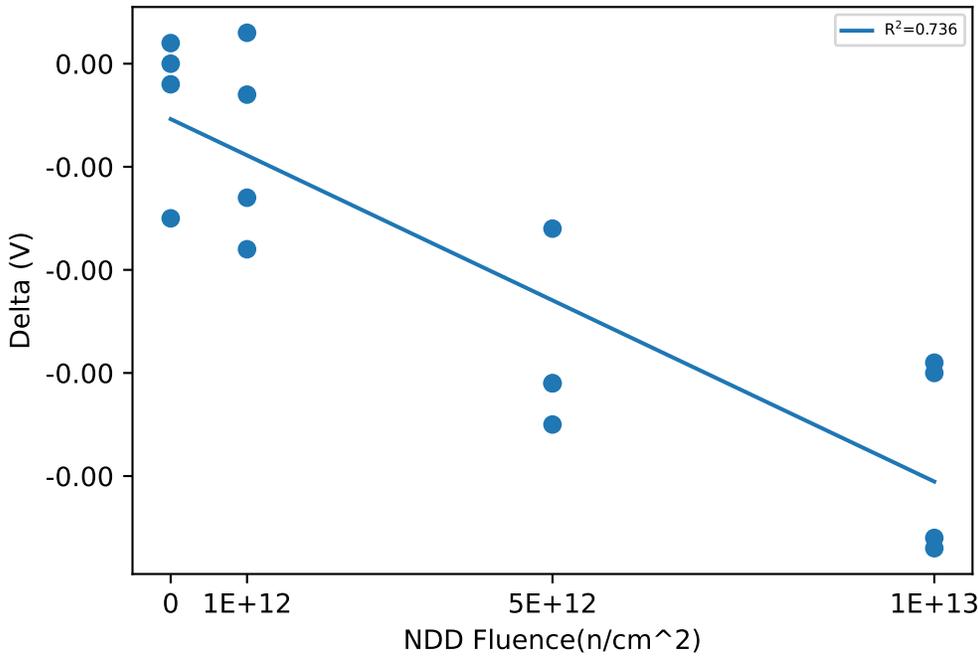
Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9915	0.99368	0.9988	0.0034673	0.9913	0.9933	0.9973	0.0027677	-0.0015	-0.000375	0.0002	0.00076757
1e+12	0.9931	0.9975	1.0022	0.0037193	0.9913	0.99672	1.0019	0.0043851	-0.0018	-0.000775	0.0003	0.00095
5e+12	0.9884	0.99067	0.993	0.0019755	0.9868	0.98785	0.9895	0.0013077	-0.0035	-0.002825	-0.0016	0.00083815
1e+13	0.9823	0.9923	0.9991	0.007126	0.9793	0.9885	0.9944	0.0064534	-0.0047	-0.0038	-0.0029	0.00098319
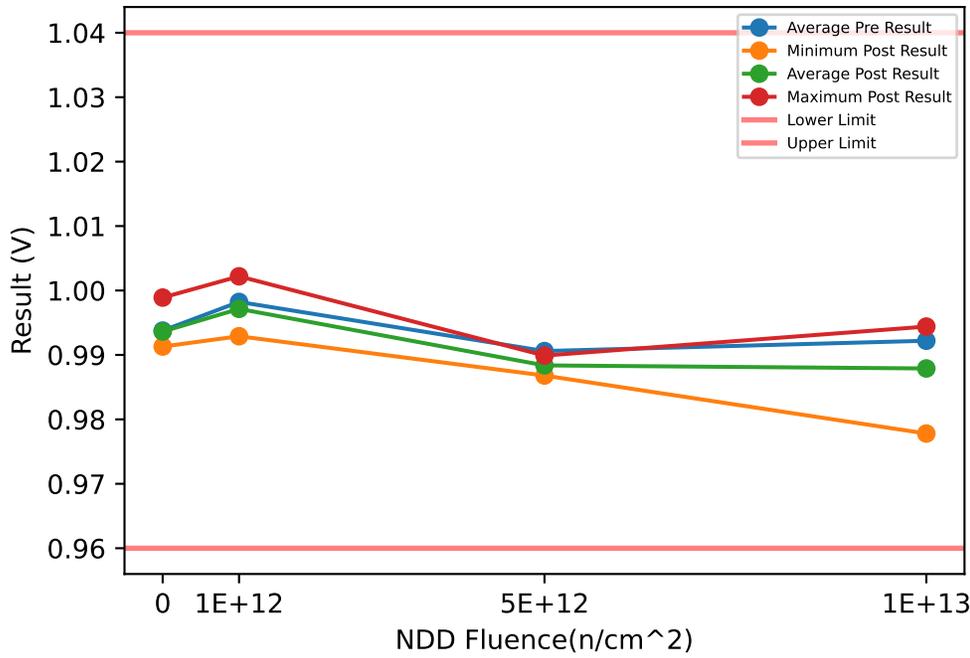
Device Test: 28.18 VOLTAGE|OC/CS/8/8/0/0/5/500kHz//@V_CS_ILIM_OC

## NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 0.96, Upper Limit = 1.04 (V))

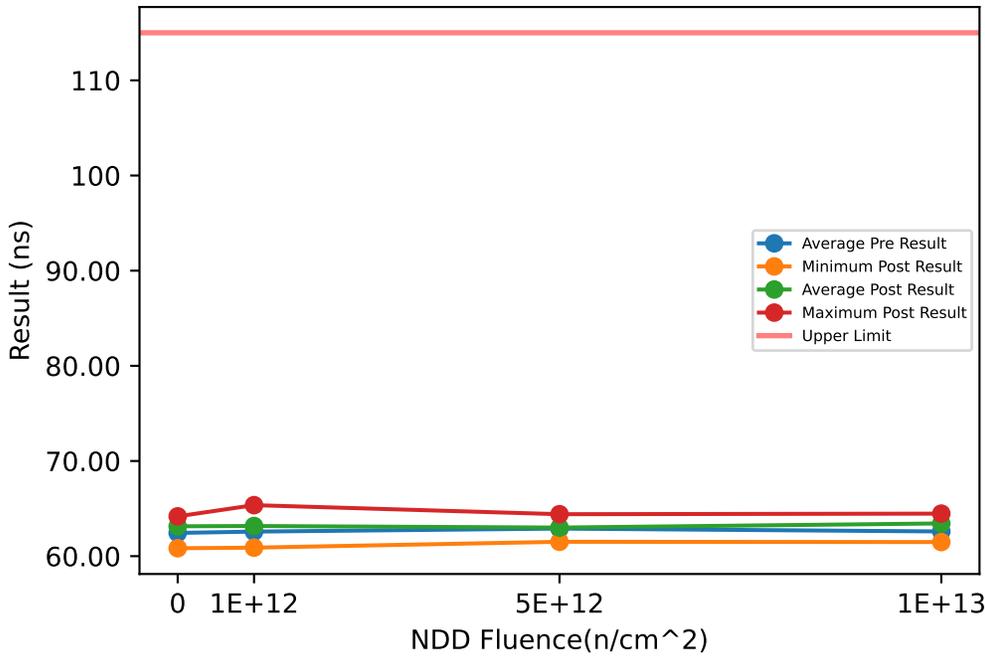| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.9928	0.9929	0.0001
2	1e+12	NDD	0.9991	0.9977	-0.0014
3	1e+12	NDD	1.0036	1.0022	-0.0014
4	1e+12	NDD	0.9974	0.9958	-0.0016
5	5e+12	NDD	0.9897	0.9883	-0.0014
6	5e+12	NDD	0.993	0.9899	-0.0031
7	5e+12	NDD	0.9899	0.9868	-0.0031
8	5e+12	NDD	0.9898	0.9885	-0.0013
9	1e+13	NDD	0.9989	0.9944	-0.0045
10	1e+13	NDD	0.9928	0.9898	-0.003
11	1e+13	NDD	0.9947	0.9896	-0.0051
12	1e+13	NDD	0.9824	0.9778	-0.0046
91	0	CORRELATION	0.9989	0.9989	0
92	0	CORRELATION	0.9929	0.9929	0
93	0	CORRELATION	0.9917	0.9913	-0.0004
94	0	CORRELATION	0.9916	0.9914	-0.0002
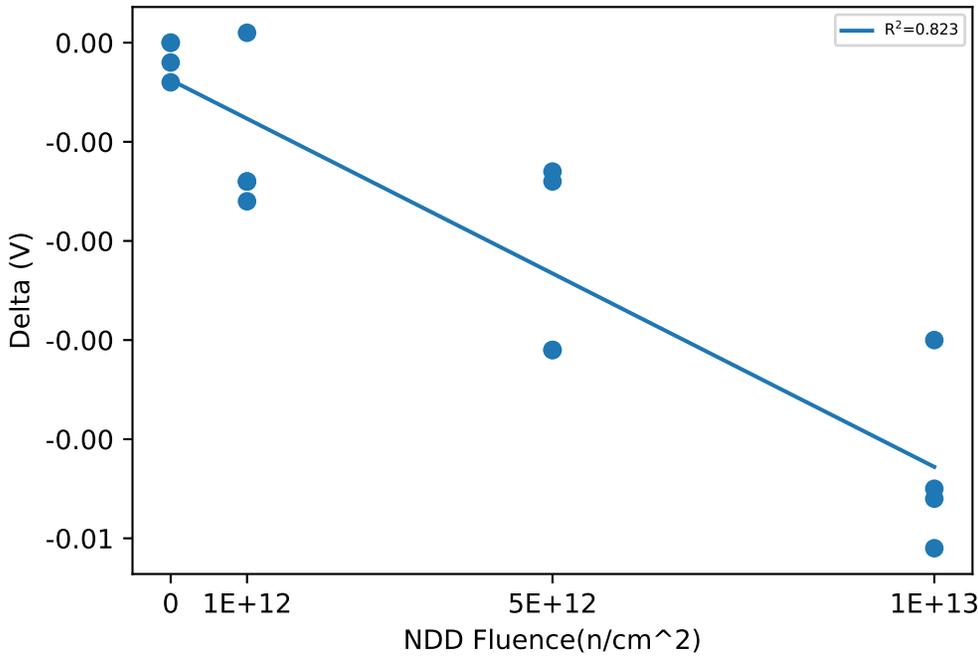
Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9916	0.99378	0.9989	0.0034673	0.9913	0.99362	0.9989	0.003592	-0.0004	-0.00015	0	0.00019149
1e+12	0.9928	0.99823	1.0036	0.0044635	0.9929	0.99715	1.0022	0.0039026	-0.0016	-0.001075	0.0001	0.00078899
5e+12	0.9897	0.9906	0.993	0.0016021	0.9868	0.98838	0.9899	0.0012685	-0.0031	-0.002225	-0.0013	0.0010112
1e+13	0.9824	0.9922	0.9989	0.0070128	0.9778	0.9879	0.9944	0.007089	-0.0051	-0.0043	-0.003	0.00090554

# Device Test: 28.19 TIMING|DELAY/CS/8/8/0/0/5/100kHz//@CS_ILIM_DELAY

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 115.0 (ns))

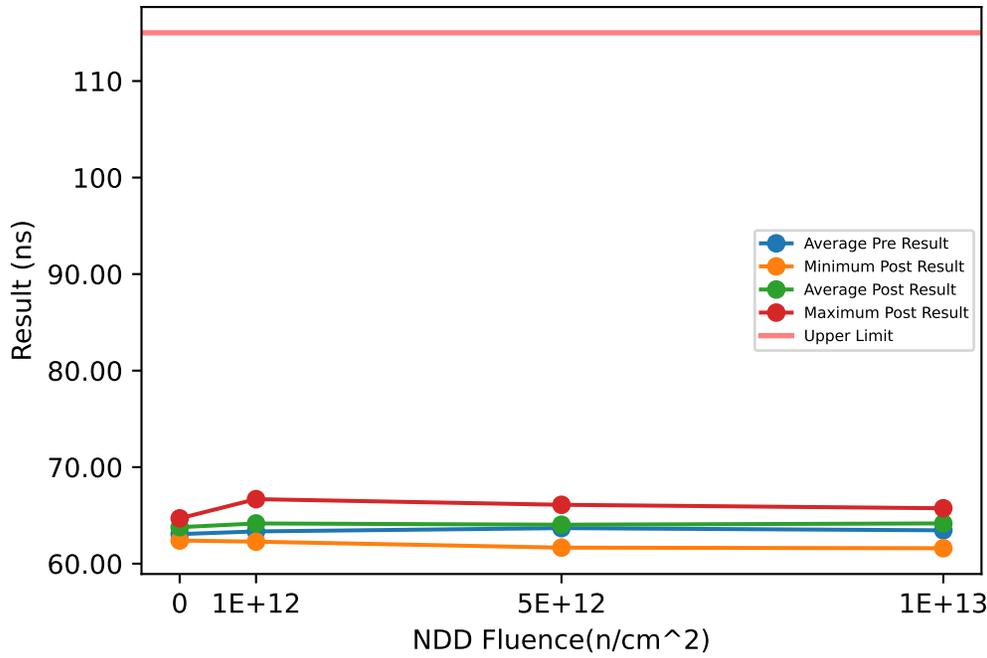| Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	61.731	62.266	0.5345
2	1e+12	NDD	60.929	60.894	-0.0355
3	1e+12	NDD	64.256	65.36	1.1034
4	1e+12	NDD	63.406	64.156	0.7499
5	5e+12	NDD	62.319	62.16	-0.1593
6	5e+12	NDD	61.386	61.511	0.1241
7	5e+12	NDD	64.096	64.409	0.313
8	5e+12	NDD	63.788	63.934	0.1457
9	1e+13	NDD	62.348	63.447	1.0986
10	1e+13	NDD	60.766	61.483	0.7163
11	1e+13	NDD	63.325	64.468	1.1437
12	1e+13	NDD	63.948	64.355	0.4071
91	0	CORRELATION	63.621	63.856	0.2347
92	0	CORRELATION	60.946	60.833	-0.1124
93	0	CORRELATION	63.155	64.183	1.0281
94	0	CORRELATION	62.045	63.681	1.6361
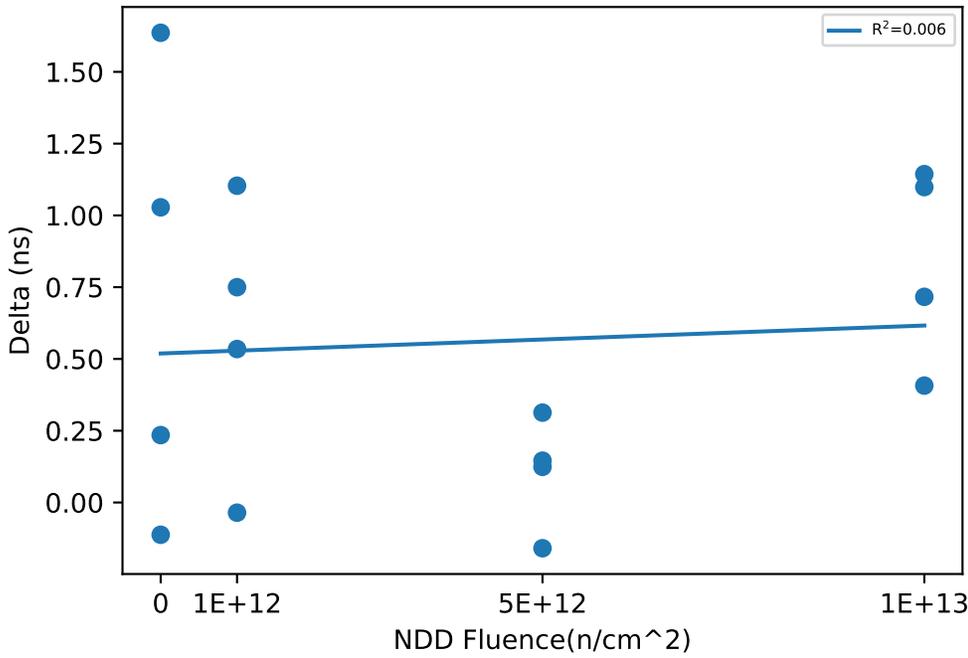
Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	60.946	62.442	63.621	1.1966	60.833	63.138	64.183	1.5507	-0.1124	0.69662	1.6361	0.78748
1e+12	60.929	62.581	64.256	1.5207	60.894	63.169	65.36	1.9804	-0.0355	0.58808	1.1034	0.47731
5e+12	61.386	62.897	64.096	1.271	61.511	63.003	64.409	1.3881	-0.1593	0.10587	0.313	0.19591
1e+13	60.766	62.597	63.948	1.3867	61.483	63.438	64.468	1.3817	0.4071	0.84143	1.1437	0.34728

Device Test: 28.20 TIMING|DELAY/CS/8/8/0/1000/5/100kHz//@CS_ILIM_DELAY

NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 115.0 (ns))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	62.826	62.567	-0.2587
2	1e+12	NDD	61.8	62.281	0.4814
3	1e+12	NDD	64.806	66.686	1.8804
4	1e+12	NDD	63.948	65.142	1.1938
5	5e+12	NDD	63.752	63.601	-0.1502
6	5e+12	NDD	62.374	61.663	-0.7111
7	5e+12	NDD	64.053	66.1	2.047
8	5e+12	NDD	64.558	64.787	0.2287
9	1e+13	NDD	63.465	63.66	0.1942
10	1e+13	NDD	61.639	61.602	-0.0378
11	1e+13	NDD	63.984	65.687	1.7027
12	1e+13	NDD	64.739	65.743	1.0043
91	0	CORRELATION	64.249	64.697	0.4481
92	0	CORRELATION	61.92	62.4	0.4799
93	0	CORRELATION	63.278	64.426	1.1483
94	0	CORRELATION	62.813	63.598	0.7845
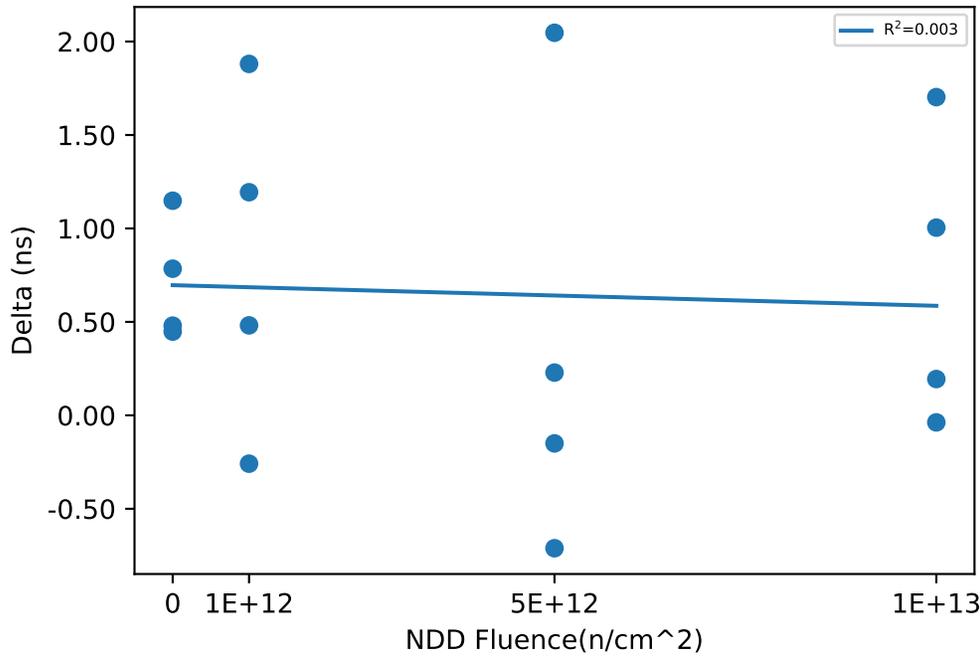
Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	61.92	63.065	64.249	0.96969	62.4	63.78	64.697	1.032	0.4481	0.7152	1.1483	0.32613
1e+12	61.8	63.345	64.806	1.311	62.281	64.169	66.686	2.1146	-0.2587	0.82423	1.8804	0.92057
5e+12	62.374	63.684	64.558	0.93469	61.663	64.038	66.1	1.8837	-0.7111	0.3536	2.047	1.1931
1e+13	61.639	63.457	64.739	1.3198	61.602	64.173	65.743	1.9693	-0.0378	0.71585	1.7027	0.79523
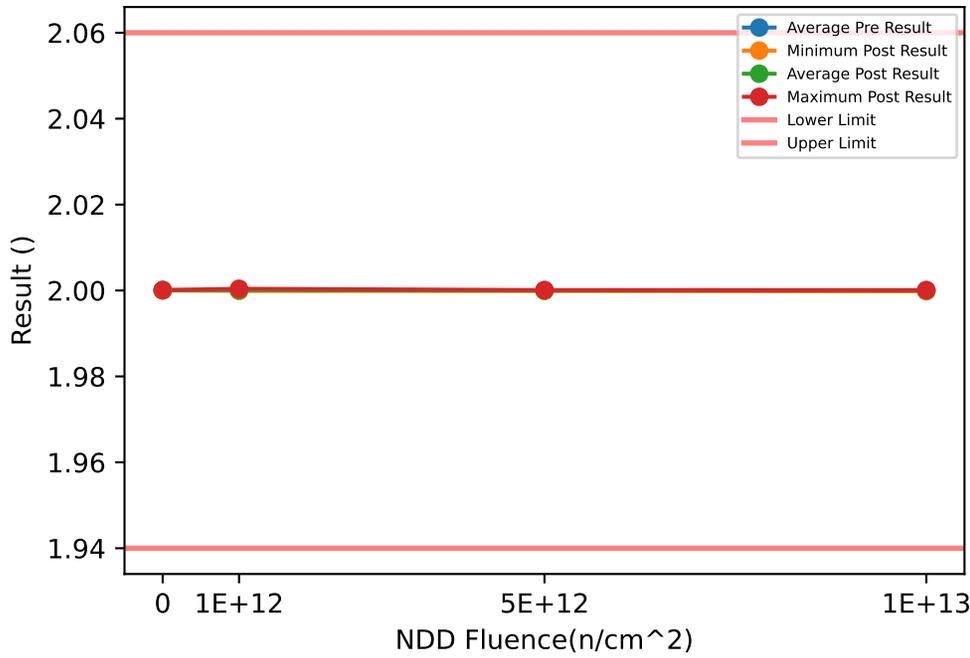
Device Test: 28.3 LEVEL|RATIO/CS/12/12/0/0/5/500kHz//@C_CS_R

## NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 1.94, Upper Limit = 2.06 ())

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	2	2	0
2	1e+12	NDD	1.9999	1.9999	0
3	1e+12	NDD	2	2.0001	0.0001
4	1e+12	NDD	2.0002	2.0004	0.0002
5	5e+12	NDD	2	2	0
6	5e+12	NDD	1.9999	2	0.0001
7	5e+12	NDD	2.0001	1.9999	-0.0002
8	5e+12	NDD	2.0001	2.0001	0
9	1e+13	NDD	2	2	0
10	1e+13	NDD	2.0001	1.9998	-0.0003
11	1e+13	NDD	2	2.0001	0.0001
12	1e+13	NDD	2	2.0001	0.0001
91	0	CORRELATION	2	2.0001	0.0001
92	0	CORRELATION	2.0001	2	-0.0001
93	0	CORRELATION	2.0001	2.0001	0
94	0	CORRELATION	2.0001	2.0001	0
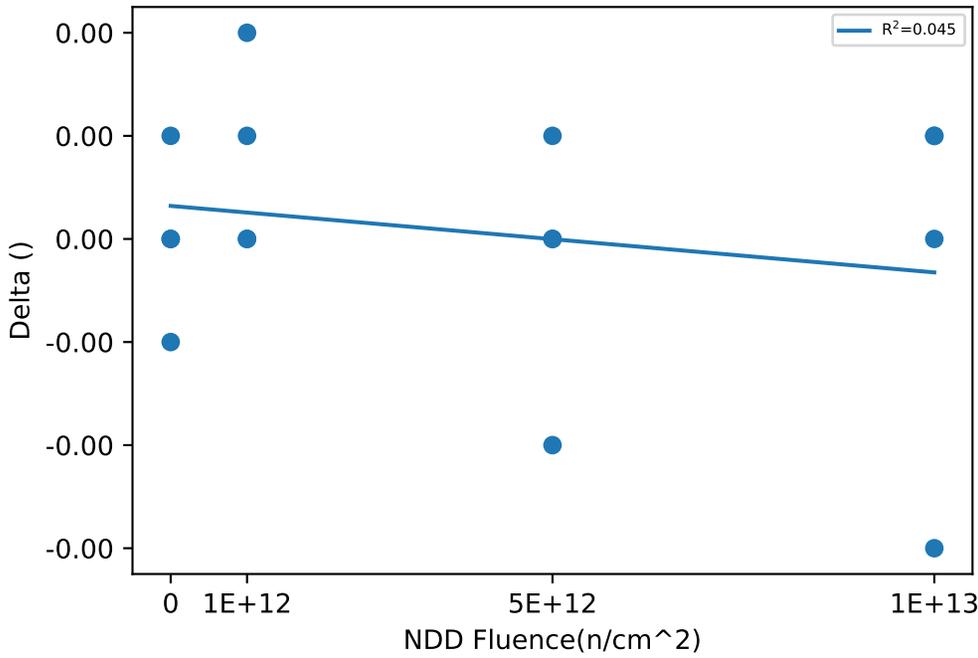
Test Statistics ()

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2	2.0001	2.0001	5e-05	2	2.0001	2.0001	5e-05	-0.0001	0	0.0001	8.165e-05
1e+12	1.9999	2	2.0002	0.00012583	1.9999	2.0001	2.0004	0.00021602	0	7.5e-05	0.0002	9.5743e-05
5e+12	1.9999	2	2.0001	9.5743e-05	1.9999	2	2.0001	8.165e-05	-0.0002	-2.5e-05	0.0001	0.00012583
1e+13	2	2	2.0001	5e-05	1.9998	2	2.0001	0.00014142	-0.0003	-2.5e-05	0.0001	0.0001893
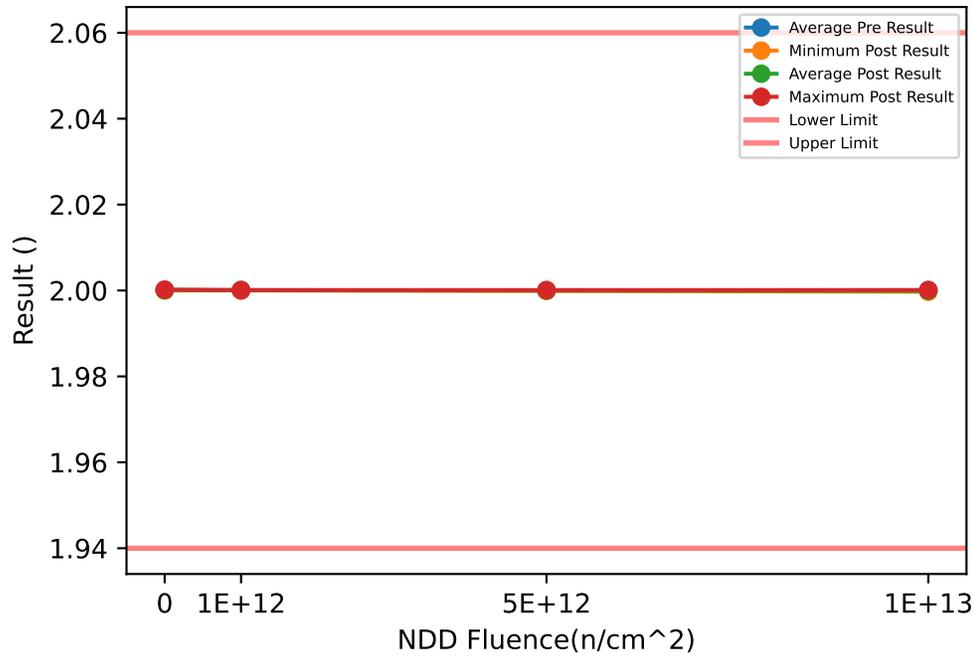
Device Test: 28.4 LEVEL|RATIO/CS/14/14/0/0/5/500kHz//@C_CS_R

NDD vs Result Stats

Legend:
- Average Pre Result
- Minimum Post Result
- Average Post Result
- Maximum Post Result
- Lower Limit
- Upper Limit

NDD vs Post - Pre Exposure Delta

$R^2=0.189$

Test Results (Lower Limit = 1.94, Upper Limit = 2.06 ())

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	2	2	0
2	1e+12	NDD	2	2.0001	0.0001
3	1e+12	NDD	2.0001	2.0001	0
4	1e+12	NDD	2.0001	2.0001	0
5	5e+12	NDD	2	2.0001	0.0001
6	5e+12	NDD	2.0001	2	-0.0001
7	5e+12	NDD	1.9999	1.9999	0
8	5e+12	NDD	2	2	0
9	1e+13	NDD	2	2	0
10	1e+13	NDD	2.0001	1.9998	-0.0003
11	1e+13	NDD	2	2.0001	0.0001
12	1e+13	NDD	2.0002	1.9997	-0.0005
91	0	CORRELATION	2	2	0
92	0	CORRELATION	2.0001	2	-0.0001
93	0	CORRELATION	2.0002	2.0002	0
94	0	CORRELATION	2.0001	2.0001	0
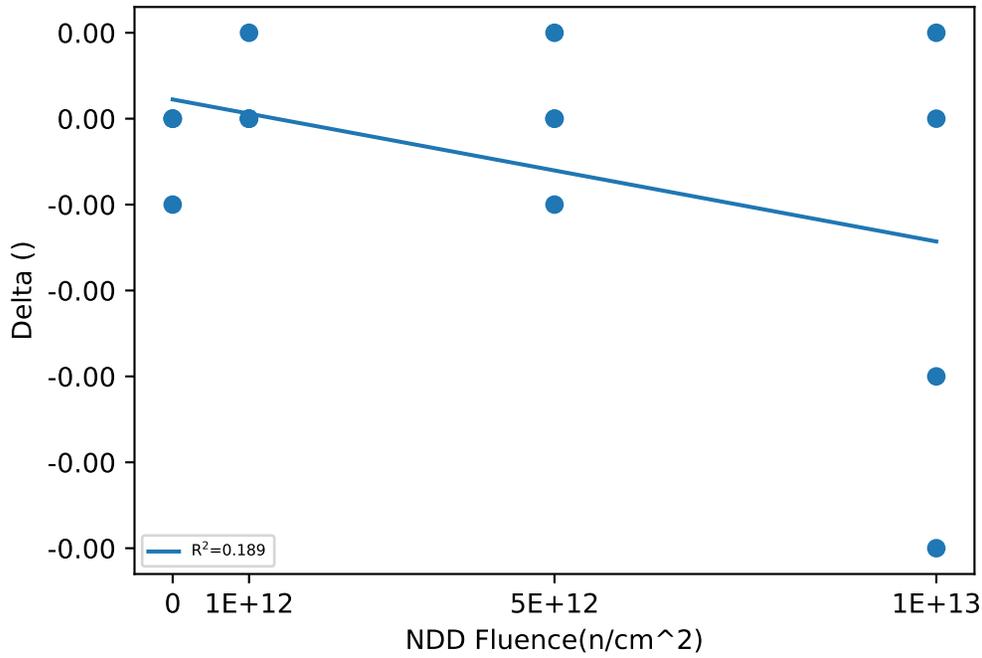
Test Statistics ()

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2	2.0001	2.0002	8.165e-05	2	2.0001	2.0002	9.5743e-05	-0.0001	-2.5e-05	0	5e-05
1e+12	2	2	2.0001	5.7735e-05	2	2.0001	2.0001	5e-05	0	2.5e-05	0.0001	5e-05
5e+12	1.9999	2	2.0001	8.165e-05	1.9999	2	2.0001	8.165e-05	-0.0001	0	0.0001	8.165e-05
1e+13	2	2.0001	2.0002	9.5743e-05	1.9997	1.9999	2.0001	0.00018257	-0.0005	-0.000175	0.0001	0.00027538
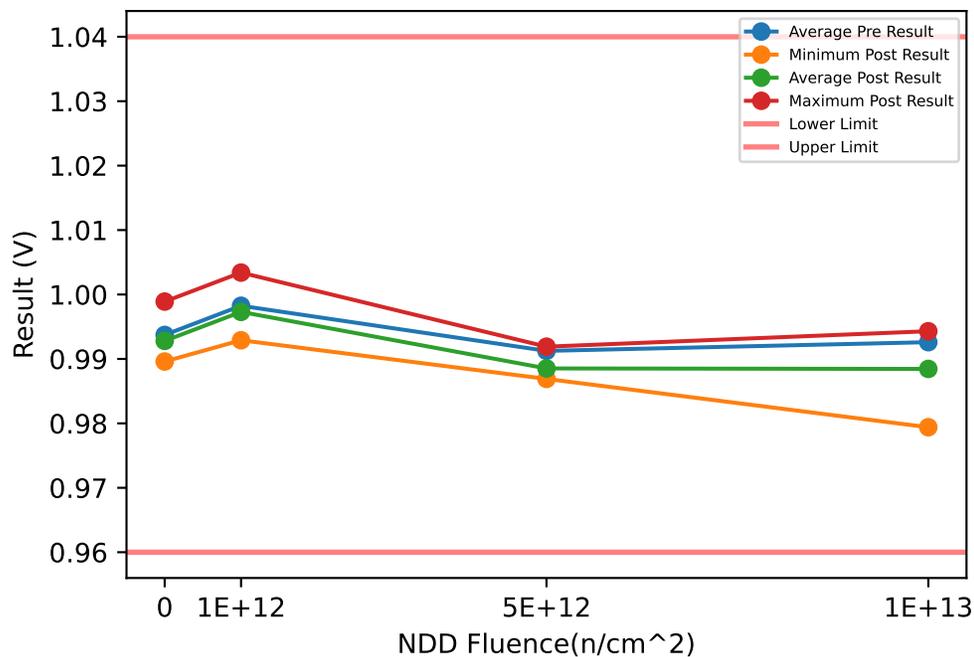
Device Test: 28.7 VOLTAGE|OC/CS/12/12/0/0/5/100kHz//@V_CS_ILIM_OC

## NDD vs Result Stats

NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 0.96, Upper Limit = 1.04 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.9928	0.9929	0.0001
2	1e+12	NDD	0.9992	0.9971	-0.0021
3	1e+12	NDD	1.0036	1.0034	-0.0002
4	1e+12	NDD	0.9974	0.9958	-0.0016
5	5e+12	NDD	0.9917	0.9883	-0.0034
6	5e+12	NDD	0.9932	0.9919	-0.0013
7	5e+12	NDD	0.9902	0.987	-0.0032
8	5e+12	NDD	0.9899	0.9869	-0.003
9	1e+13	NDD	1.0003	0.9943	-0.006
10	1e+13	NDD	0.9929	0.9903	-0.0026
11	1e+13	NDD	0.9948	0.9898	-0.005
12	1e+13	NDD	0.9824	0.9794	-0.003
91	0	CORRELATION	0.9989	0.9989	0
92	0	CORRELATION	0.9929	0.9929	0
93	0	CORRELATION	0.9915	0.9898	-0.0017
94	0	CORRELATION	0.9916	0.9896	-0.002
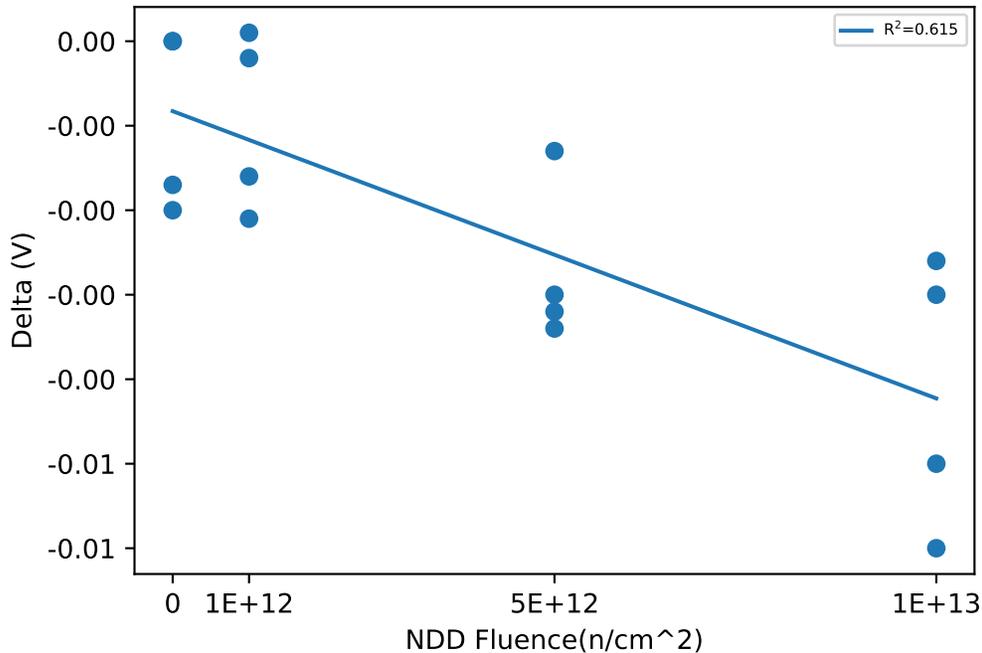
Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9915	0.99372	0.9989	0.0035084	0.9896	0.9928	0.9989	0.0043382	-0.002	-0.000925	0	0.0010751
1e+12	0.9928	0.99825	1.0036	0.0044703	0.9929	0.9973	1.0034	0.0044294	-0.0021	-0.00095	0.0001	0.0010661
5e+12	0.9899	0.99125	0.9932	0.0015199	0.9869	0.98852	0.9919	0.0023386	-0.0034	-0.002725	-0.0013	0.00096393
1e+13	0.9824	0.9926	1.0003	0.0074891	0.9794	0.98845	0.9943	0.0063606	-0.006	-0.00415	-0.0026	0.0016197
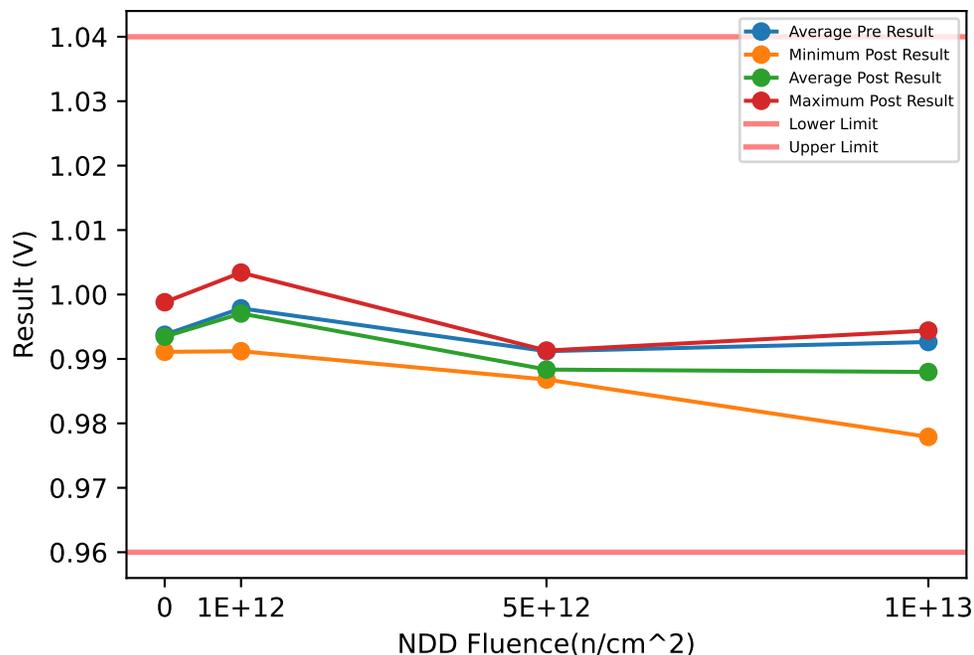
Device Test: 28.8 VOLTAGE|OC/CS/14/14/0/0/5/100kHz//@V_CS_ILIM_OC

NDD vs Result Stats

## NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 0.96, Upper Limit = 1.04 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.9931	0.9912	-0.0019
2	1e+12	NDD	0.9988	0.9977	-0.0011
3	1e+12	NDD	1.0021	1.0034	0.0013
4	1e+12	NDD	0.9974	0.9959	-0.0015
5	5e+12	NDD	0.9917	0.9883	-0.0034
6	5e+12	NDD	0.9932	0.9913	-0.0019
7	5e+12	NDD	0.99	0.9868	-0.0032
8	5e+12	NDD	0.9899	0.987	-0.0029
9	1e+13	NDD	1.0004	0.9944	-0.006
10	1e+13	NDD	0.993	0.9898	-0.0032
11	1e+13	NDD	0.9947	0.9898	-0.0049
12	1e+13	NDD	0.9824	0.9779	-0.0045
91	0	CORRELATION	0.9989	0.9988	-0.0001
92	0	CORRELATION	0.9929	0.9926	-0.0003
93	0	CORRELATION	0.9915	0.9913	-0.0002
94	0	CORRELATION	0.9917	0.9911	-0.0006
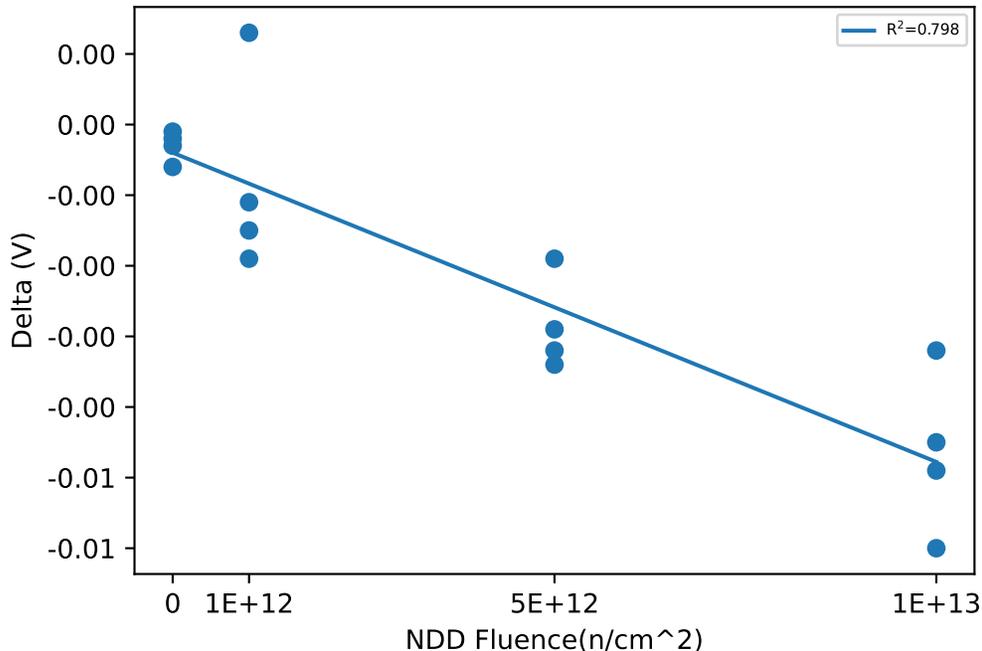
Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9915	0.99375	0.9989	0.0034886	0.9911	0.99345	0.9988	0.0036281	-0.0006	-0.0003	-0.0001	0.00021602
1e+12	0.9931	0.99785	1.0021	0.0037296	0.9912	0.99705	1.0034	0.0050428	-0.0019	-0.0008	0.0013	0.0014376
5e+12	0.9899	0.9912	0.9932	0.0015684	0.9868	0.98835	0.9913	0.0020761	-0.0034	-0.00285	-0.0019	0.00066583
1e+13	0.9824	0.99262	1.0004	0.0075155	0.9779	0.98798	0.9944	0.007058	-0.006	-0.00465	-0.0032	0.0011561
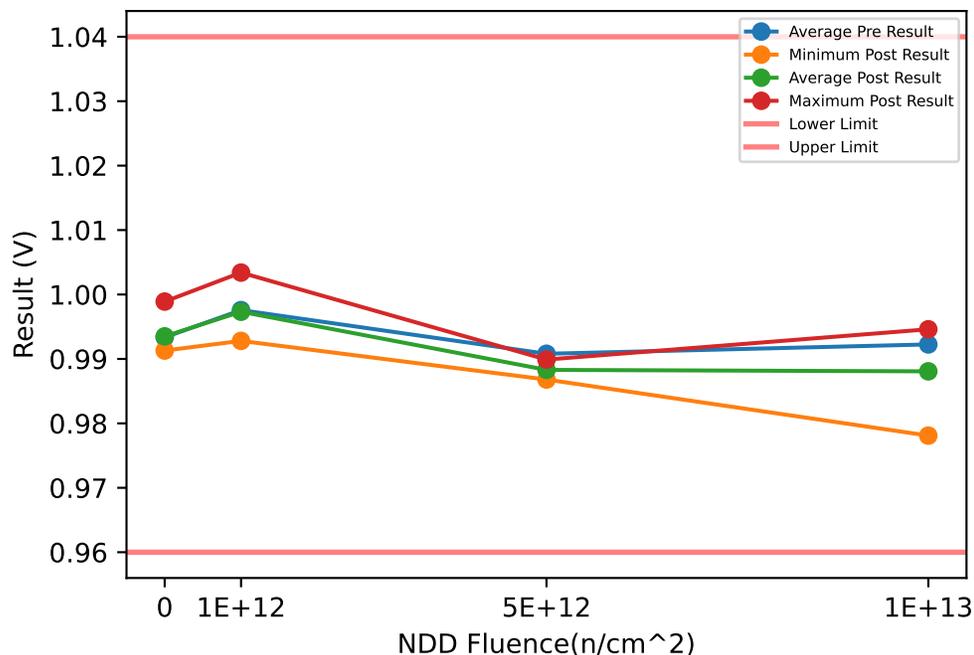
Device Test: 28.9 VOLTAGE|OC/CS/12/12/0/0/5/500kHz//@V_CS_ILIM_OC

NDD vs Result Stats

Legend:
- Average Pre Result
- Minimum Post Result
- Average Post Result
- Maximum Post Result
- Lower Limit
- Upper Limit

NDD vs Post - Pre Exposure Delta

R²=0.790

Test Results (Lower Limit = 0.96, Upper Limit = 1.04 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.9931	0.9928	-0.0003
2	1e+12	NDD	0.9992	0.9971	-0.0021
3	1e+12	NDD	1.0021	1.0034	0.0013
4	1e+12	NDD	0.9959	0.996	0.0001
5	5e+12	NDD	0.9917	0.9884	-0.0033
6	5e+12	NDD	0.9932	0.9899	-0.0033
7	5e+12	NDD	0.9884	0.9868	-0.0016
8	5e+12	NDD	0.9899	0.9881	-0.0018
9	1e+13	NDD	0.9988	0.9946	-0.0042
10	1e+13	NDD	0.9933	0.9898	-0.0035
11	1e+13	NDD	0.9946	0.9898	-0.0048
12	1e+13	NDD	0.9823	0.9781	-0.0042
91	0	CORRELATION	0.9988	0.9989	0.0001
92	0	CORRELATION	0.9932	0.9925	-0.0007
93	0	CORRELATION	0.9898	0.9913	0.0015
94	0	CORRELATION	0.9916	0.9913	-0.0003
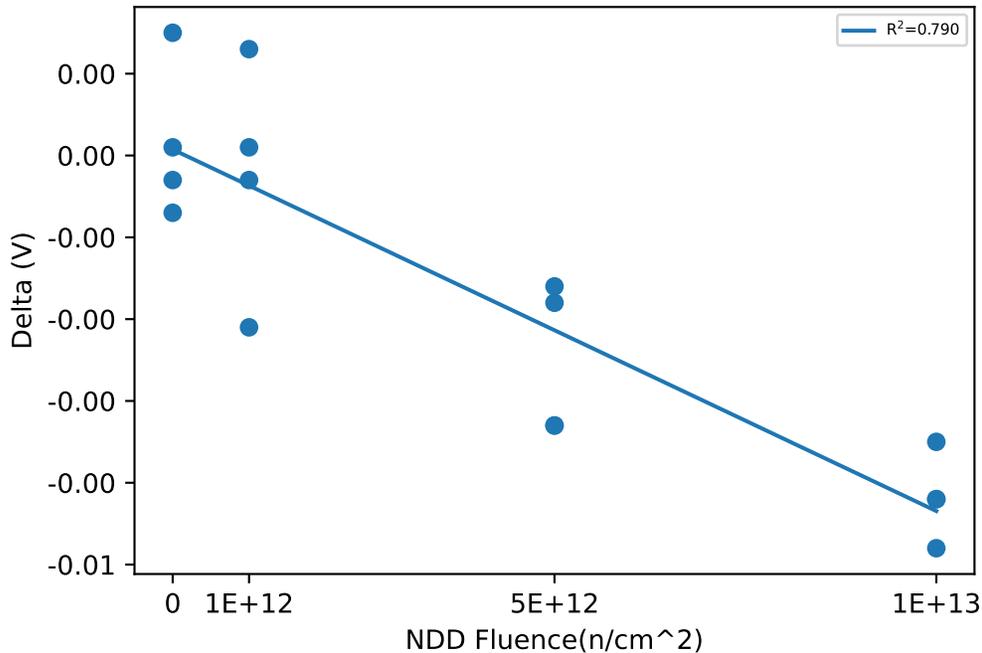
Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9898	0.99335	0.9988	0.0038897	0.9913	0.9935	0.9989	0.0036442	-0.0007	0.00015	0.0015	0.00095743
1e+12	0.9931	0.99757	1.0021	0.0039135	0.9928	0.99733	1.0034	0.0044418	-0.0021	-0.00025	0.0013	0.0014083
5e+12	0.9884	0.9908	0.9932	0.0020928	0.9868	0.9883	0.9899	0.0012728	-0.0033	-0.0025	-0.0016	0.00092736
1e+13	0.9823	0.99225	0.9988	0.0070363	0.9781	0.98808	0.9946	0.0070244	-0.0048	-0.004175	-0.0035	0.00053151

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